

NASA Technical Memorandum 104759

Analysis of Impactor Residues in Tray Clamps from the Long Duration Exposure Facility

Part 1: Clamps from Bay "A" of the Satellite

Ronald P. Bernhard
*Planetary Sciences Department
Lockheed Engineering and Science Company
Houston, TX 77058*

Michael E. Zolensky
*Office of the Curator/Solar System Exploration Division
NASA/Johnson Space Center
Houston, TX 77058*



**National Aeronautics and
Space Administration**

**Solar System Exploration
Division
1993**



Contents

Section	Page
Introduction	1
LDEF Tray Clamps	2
Results	2
References	3
Appendix	A-1

PRECEDING PAGE BLANK NOT FILMED

11-11-68

Figures

Figure		Page
1	<p>A photograph taken of the trailing/Earth edge of the Long Duration Exposure Facility (A03) during the STS-32 retrieval mission. The arrows placed on the photograph show the location of clamps used to hold experiment trays in place during their exposure in low Earth orbit. The circles or round patches on some of the clamps are test paint coupons. Several possess impact craters but, because of surface contamination impact residues, these were not characterized here</p>	4
2	<p>This diagram illustrates the numbering scheme used to label LDEF experiments by Bay and Row location. LDEF was a cylinder-shaped satellite with Row 1 being adjacent to Row 12, Bay A being on the Earth end and Bay F positioned on the space facing end. While in orbit, Row 9 was in the ram direction or the leading edge, with Row 3 being on the trailing edge of motion. Clamps examined for this report are designated by dark fill</p>	5
3	<p>This schematic illustrates the numbering plan and positioning layout of tray clamps and bolt holes on the LDEF satellite. The bolt hole locations help to align the clamp to find the lower left orientation corner (0,0)</p>	6
4	<p>Secondary electron image of several impact-like flaws detected on the clamp surface. Features like these are quite abundant and are thought to be flaws acquired during the manufacturing and handling of the clamps</p>	7
5	<p>This very low velocity feature is similar to that in figure 3. During high magnification optical examination, this specimen appeared to be a typical hypervelocity impact crater. SEM examination determined its probable origin to be a handling flaw</p>	7
6	<p>Surface flaws from chromic-anodization were also present on many of the clamps. The chemistry of such a flaw shows high levels of Si, Mg, Cl, and S, which are easily recognized by SEM/EDX analysis</p>	8
7	<p>An example of a linear, repetitive-type pattern that occurred during the fabrication or preflight handling of clamps and other LDEF hardware⁽¹⁾</p>	8
8	<p>Many of the impacts analyzed by SEM/EDXA had no residue detected. These impact features are categorized as being unknown in origin. During analysis, no peaks above background were discernible; only the typical clamp materials were present. This spectra illustrates the typical composition of impacts with no detectable residue found</p>	9

Figure

Page

9	Histogram illustrating the determined impactor type versus the impact crater diameter. Samples listed as being contaminated contain significant amounts of foreign material and projectile remnants that are not easily identified	10
---	--	----

Acronyms

EDXA	energy dispersive X-ray analysis
FOILS	Facility for Optical Inspection of Large Surfaces
JSC	NASA/Lyndon B. Johnson Space Center
LDEF	Long Duration Exposure Facility
LEO	low Earth orbit
M&D SIG	Meteoroid & Debris Special Investigation Group
SEM	scanning electron microscopy

Introduction

The Long Duration Exposure Facility (LDEF) was placed in low Earth orbit (LEO) in 1984 and was recovered 5.7 years later. The LDEF hosted several individual experiments that were specifically designed to characterize critical aspects of meteoroid and debris environment in LEO. It was realized from the beginning, however, that the most efficient use of the satellite would be to examine the entire surface for impact features. In this regard, particular interest has centered on common exposed materials that faced in all LDEF pointing directions. Among the most important of these materials is the tray clamps. Therefore, in an effort to understand the nature of particulates in LEO and their effects on spacecraft hardware better, we are analyzing residues found in impact features on LDEF tray clamp surfaces. This catalog presents all data from clamps from Bay A of the LDEF. Subsequent catalogs will include clamps from succeeding bays of the satellite.

All LDEF experiment trays were held in place by a series of aluminum clamps (fig. 1). Each clamp had an exposed area of approximately 58 cm². One-half of the LDEF tray clamps have been archived at the NASA/Johnson Space Center (JSC) by the Meteoroid & Debris Special Investigation Group (M&D SIG). These archives are available for study by qualified investigators. For more information regarding these materials, contact the JSC Curatorial Facility. The remaining half of the clamps are being studied by the LDEF Materials Space Investigation Group.

Optical scanning of clamps—beginning with Bay A Row 01 and working through the entire satellite—is being documented in the Facility for Optical Inspection of Large Surfaces (FOILS) at JSC to locate and document impact features that are as small as 30 microns. These impacts are then examined by scanning electron microscopy/energy dispersive X-ray analysis (SEM/EDXA) to characterize further those features that contain appreciable impactor residue. Based upon the bulk composition of those residues and using criteria developed at JSC^[2], we have made a preliminary discrimination between micrometeoroid- and space debris-containing impact features. These data are in a catalog format that includes (1) an optical photograph of each clamp, (2) a secondary electron image of the impact, (3) associated parameters such as impact feature size, (4) an EDXA plot of the residue, (5) impactor origin (if applicable), and (6) a curatorial number that will facilitate requests for specific impact features by interested investigators. All results are being input into the M&D SIG computerized database, which documents all LDEF meteoroid and debris results and is accessible to investigators via SPAN, Internet, or modem.^[2]

LDEF Tray Clamps

LDEF experiment trays were held in place by a series of chromic-anodized aluminum (6061-T6) clamps (fig. 2). Eight clamps were used to attach the experiment trays on each of the 12 sides of the LDEF, while experiment trays on the Earth and space ends were held in place by 12 clamps. Each clamp was fastened to the spacecraft frame using three stainless-steel hex bolts. Clamps exposed an area of approximately 58 cm² each (4.8 cm × 12.7 cm × 0.45 cm, minus the bolt coverage). All 774 LDEF clamps were surveyed for impact features greater than 0.5 mm in diameter during experiment tray deintegration at the NASA/Kennedy Space Center. Some 337 out of 774 LDEF tray clamps have been archived by the M&D SIG in the Curatorial Facility at JSC and are available for scientific examination by qualified individuals.

A clamp numbering scheme was devised that would provide hardware location information with respect to its position within a particular bay (fig. 2). From the labeling scheme, it can be seen that a clamp occupying position 1 of Bay A02 would be identified by the label A02-C01, with A02 indicating the experiment location of Bay "A" and Row "02," and with C01 interpreted as "C" for the clamp and "01" being the clamp number. Each clamp uses a Cartesian coordinate system to reference impact locations on exposed surfaces. The X and Y coordinates were measured in millimeters using a standard origin assigned by the M&D SIG at the lower left corner of each clamp (fig. 3).

Results

Each of the clamps was optically scanned. All impact features greater than 40 microns (and some as small as 30 microns) were labeled and their position was documented. After scanning, an optical photograph was taken of the clamp illustrating each of the impact features located optically. Clamps that contained no detectable impact features are not included in this catalog. These clamps are A02-C01, -C03, -C05, -C06, and A03-C06 and A04-C06, which are still available to individuals for further analysis. SEM/EDXA was then conducted on each feature that has been identified optically. Not all features identified are high-velocity impacts. In some cases, because of resolution limits during optical inspection, clamp manufacturing flaws, handling flaws, and contamination spots were mistakenly identified as impact features. During SEM/EDXA analysis, these features were properly identified and labeled as such (figs. 4 through 7). These features include craters and pits caused during the manufacturing and handling of the clamps. When clamp edges were ground

smooth, abrasive grit could become trapped between the clamps when they were stacked one upon the other. Movement caused these grains to roll and leave tracks and pits.^[1] The secondary electron images were obtained at 30 deg from normal. Because the initial intent of this survey was to identify only those impacts that contained large amounts of micrometeoritic residue, a minimal amount of time was spent analyzing for small or unobvious projectile remnants. The EDX spectra obtained were qualitative but served to provide a basic classification of either "natural" or "manmade" for residues, although many of the impacts are classified as having no definite origin. Clamp impacts that have no detectable residues by techniques were used to display a composition typical of the clamp aluminum alloy. Although the exact composition differed slightly from example to example, these spectra were recognizably the same. For this reason, a standard clamp aluminum alloy spectrum is displayed in figure 8. Throughout the catalog, features containing no detectable residue will reference this spectra. The criteria used to determine impactor origin are described at length in another publication.^[2] Figure 9 summarizes the survey residue classification results for our clamp analyses in histogram form. We believe that further, more detailed analyses will undoubtedly uncover evidence of impactor residues in many of the presently unclassified impact craters. The support of such subsequent analysis is our primary objective in publishing this catalog. A factor hindering our analyses is the fact that the clamps have all been anodized, a process that deposits a surface layer of Si, Mg, and S—all of which are important elements for the discrimination of natural from manmade materials. This contamination has been properly considered as background, but in many instances its presence makes characterization of the residues extremely difficult.

References

- [1] Redd, Cecil; and Zolensky, Mike E. (1991) *Too exposed* (Scientific correspondence). *Nature* 352, page 289.
- [2] Zolensky, M. E.; Zook, H.; Atkinson, D.; Coombs, C.; Dardano, C.; See, T.; Simon, C.; and Kinard W. (1993) *Interim report of the Meteoroid and Debris Special Investigation Group*. From *Proceedings of the 2nd LDEF Post-Retrieval Conference*, eds., A. Levine and W. Kinard. In press (available from the LDEF Project Office at NASA/Langley, mail stop 404).



FIGURE 1. A photograph taken of the trailing/Earth edge of the Long Duration Exposure Facility (A03) during the STS-32 retrieval mission. The arrows placed on the photograph show the location of clamps used to hold experiment trays in place during their exposure in low Earth orbit. The circles or round patches on some of the clamps are test paint coupons. Several possess impact craters but, because of surface contamination impact residues, these were not characterized here.

SPACE END

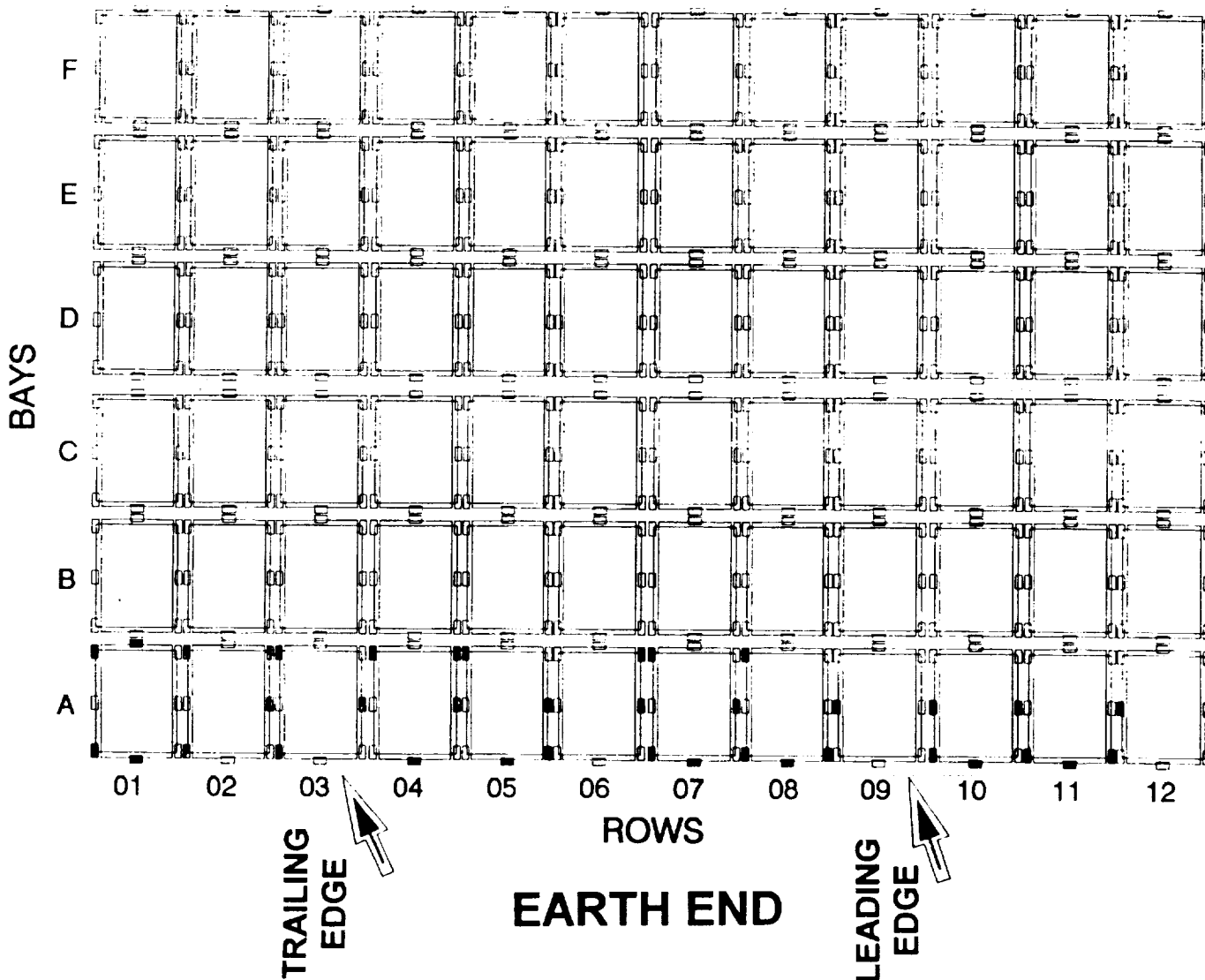


FIGURE 2. This diagram illustrates the numbering scheme used to label LDEF experiments by Bay and Row location. LDEF was a cylinder-shaped satellite with Row 1 being adjacent to Row 12, Bay A being on the Earth end and Bay F positioned on the space facing end. While in orbit, Row 9 was in the ram direction or the leading edge, with Row 3 being on the trailing edge of motion. Clamps examined for this report are designated by dark fill.

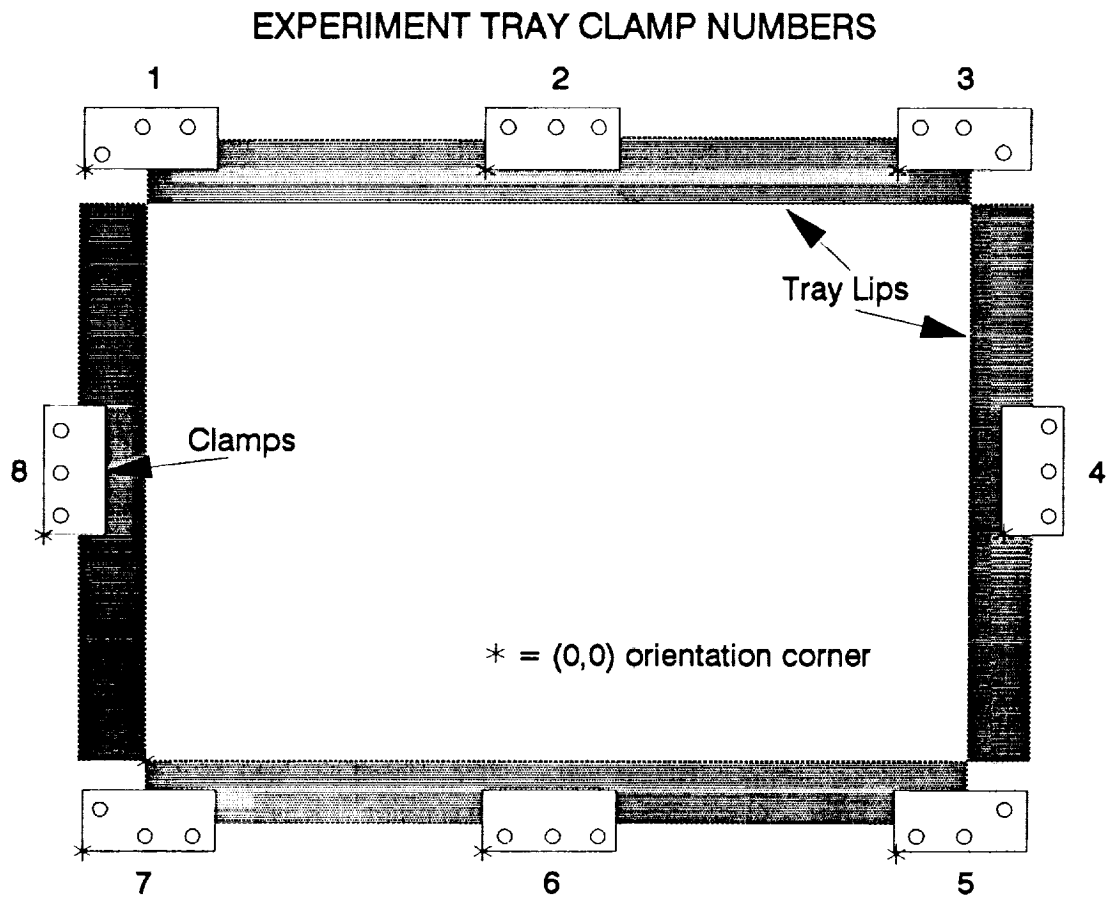


FIGURE 3. This schematic illustrates the numbering plan and positioning layout of tray clamps and bolt holes on the LDEF satellite. The bolt hole locations help to align the clamp to find the lower left orientation corner (0,0).

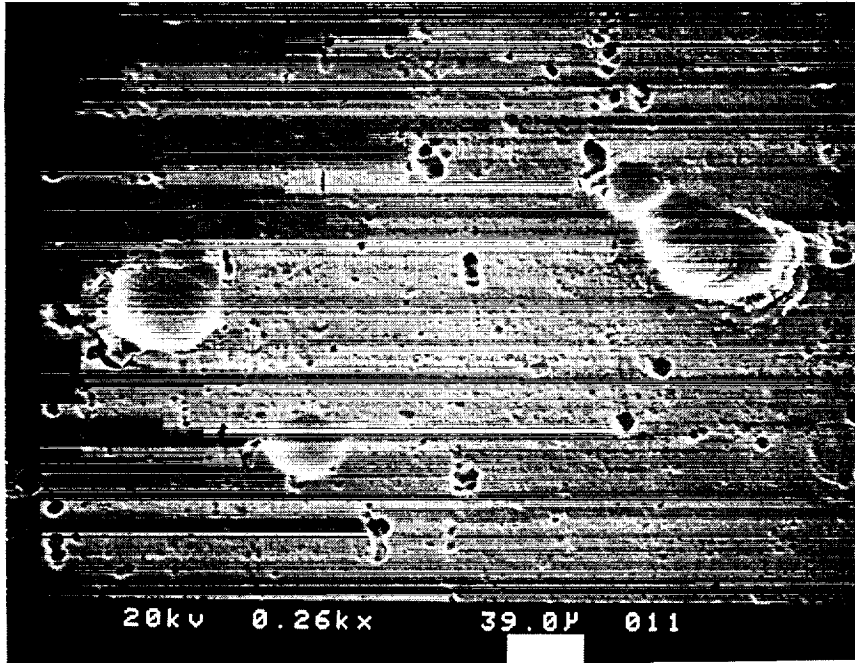


FIGURE 4. Secondary electron image of several impact-like flaws detected on the clamp surface. Features like these are quite abundant and are thought to be flaws acquired during the manufacturing and handling of the clamps.

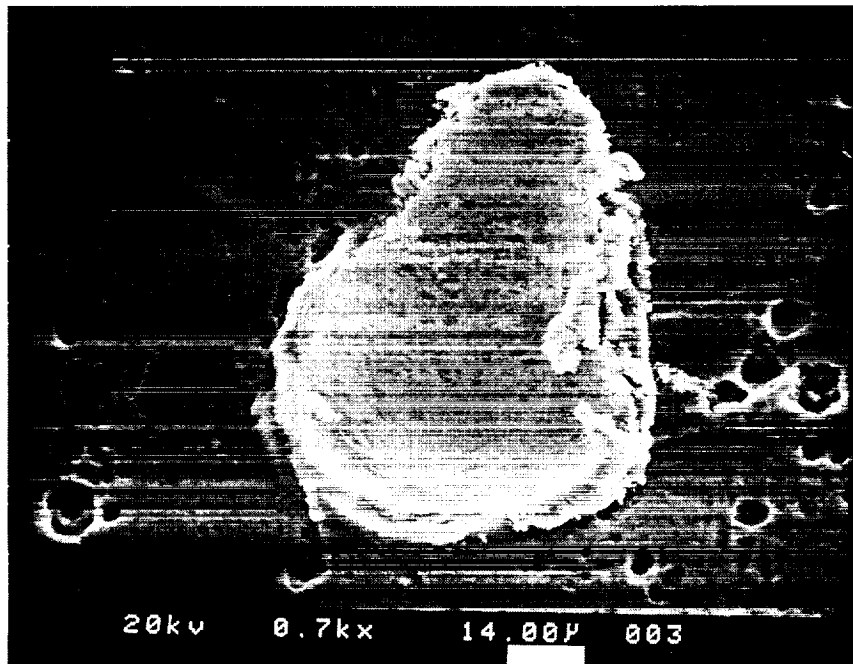


FIGURE 5. This very low velocity feature is similar to that in figure 3. During high magnification optical examination, this specimen appeared to be a typical hypervelocity impact crater. SEM examination determined its probable origin to be a handling flaw.

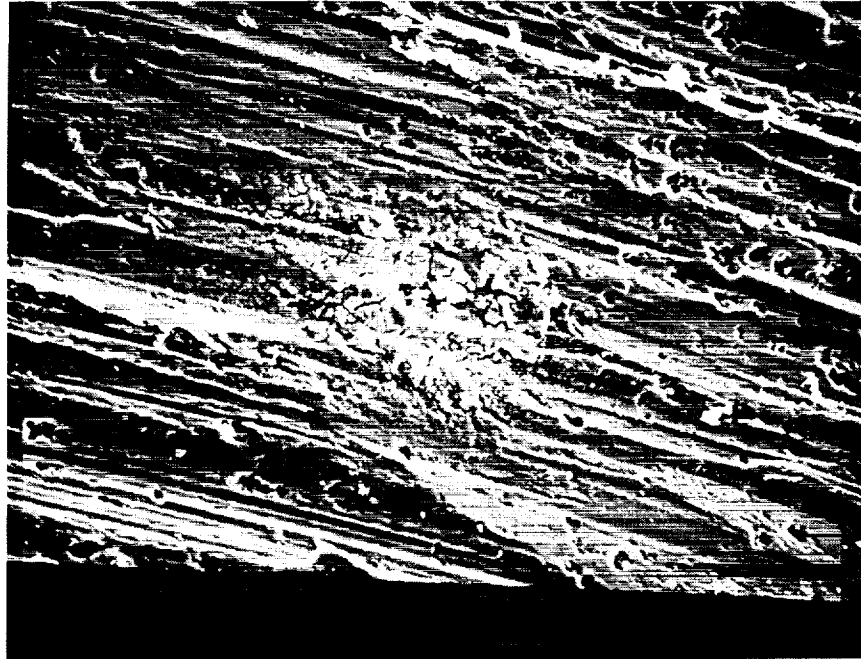


FIGURE 6. Surface flaws from chromic-anodization were also present on many of the clamps. The chemistry of such a flaw shows high levels of Si, Mg, Cl, and S, which are easily recognized by SEM/EDX analysis.

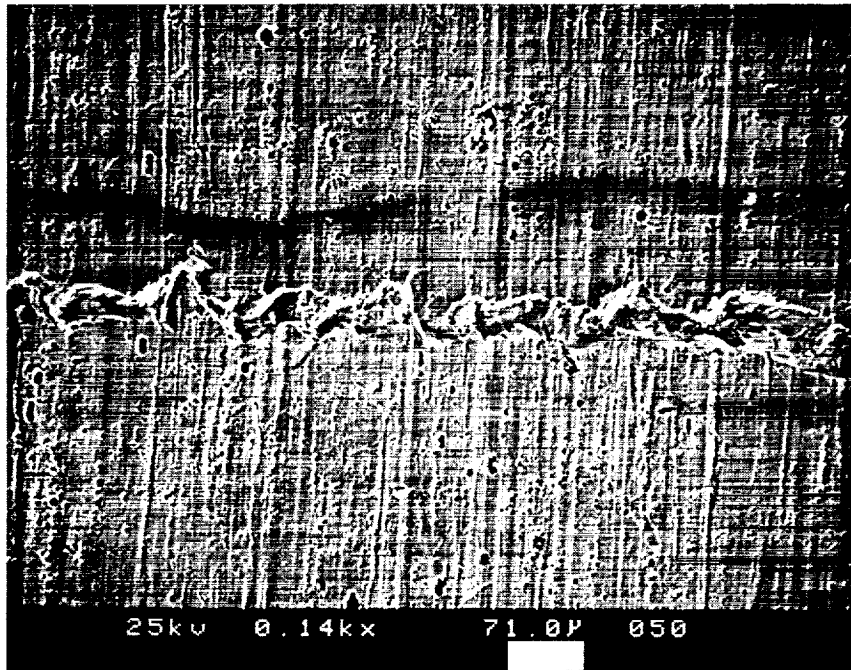


FIGURE 7. An example of a linear, repetitive-type pattern that occurred during the fabrication or preflight handling of clamps and other LDEF hardware.^[1]

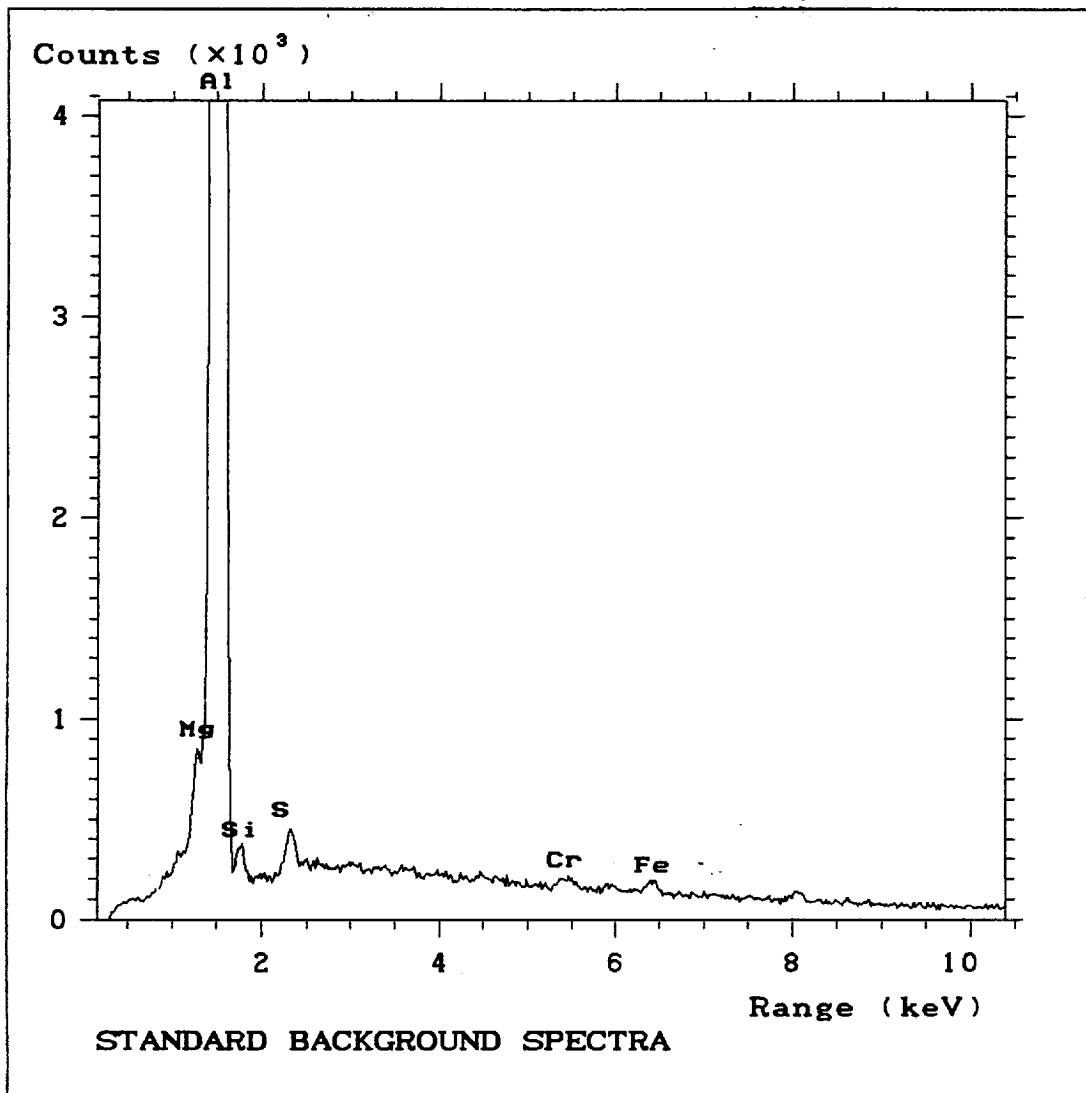


FIGURE 8. Many of the impacts analyzed by SEM/EDXA had no residue detected. These impact features are categorized as being unknown in origin. During analysis, no peaks above background were discernible; only the typical clamp materials were present. This spectra illustrates the typical composition of impacts with no detectable residue found.

TRAY CLAMP IMPACTS

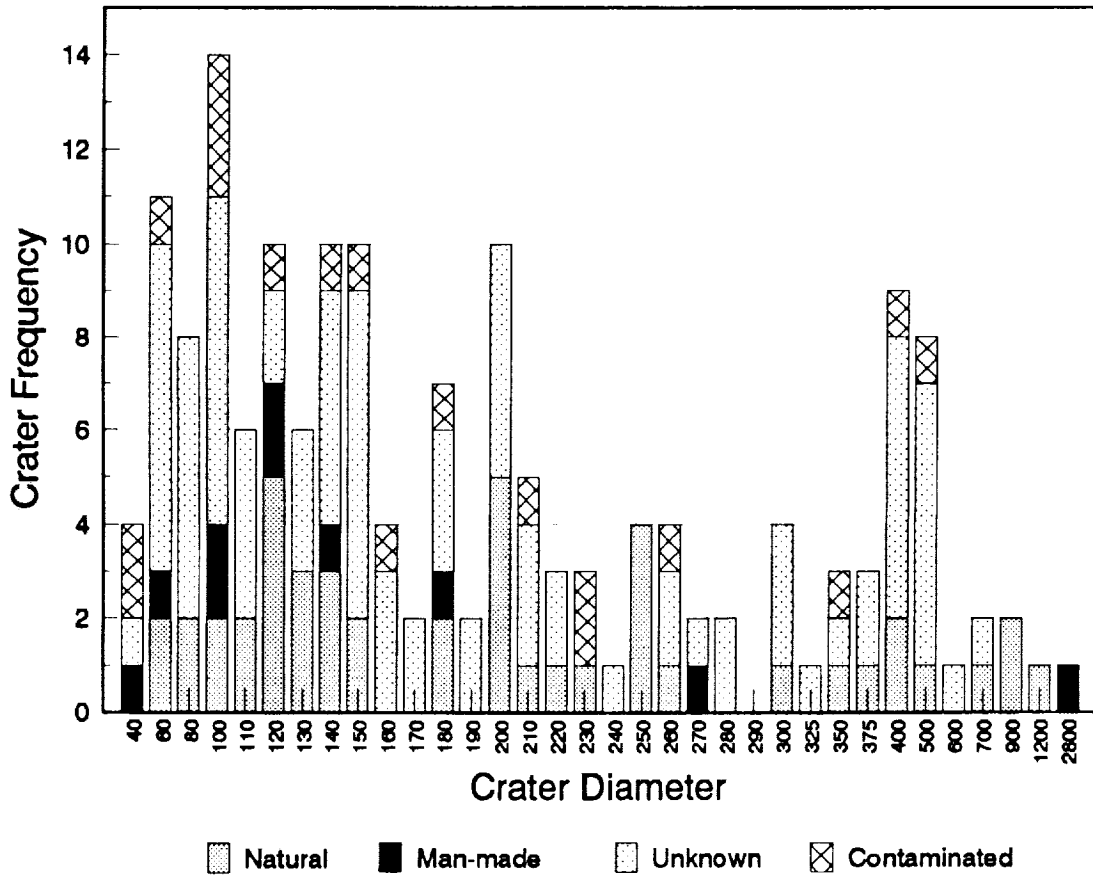
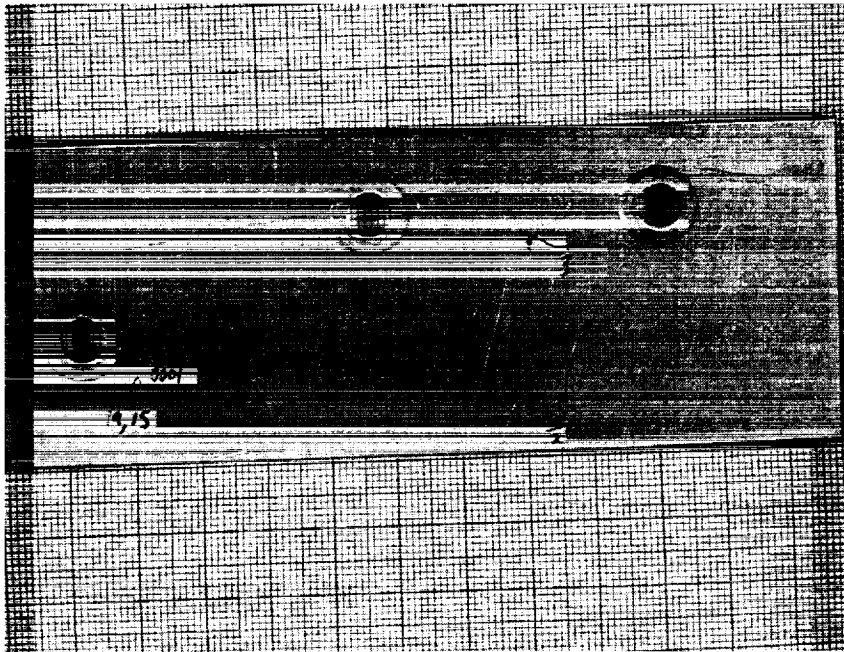


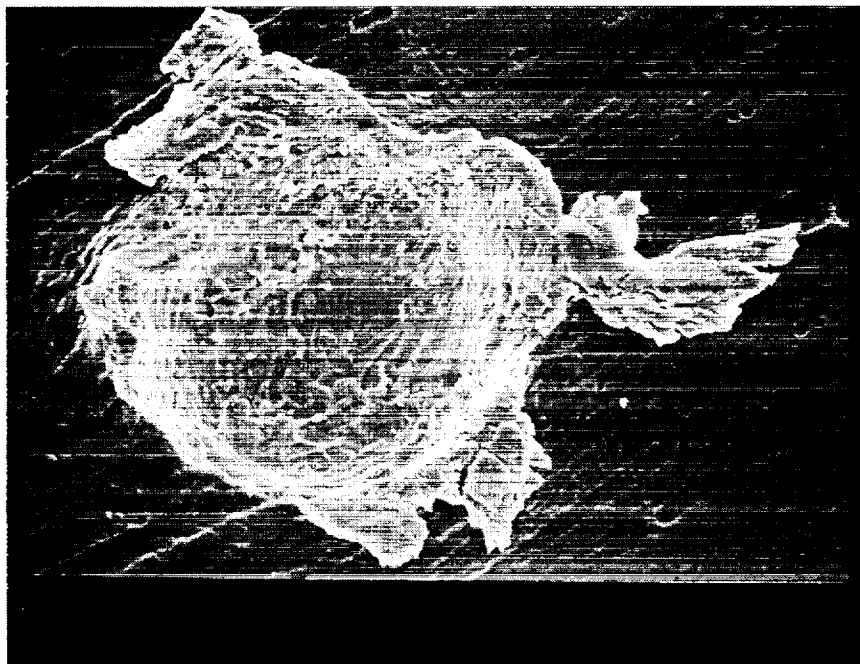
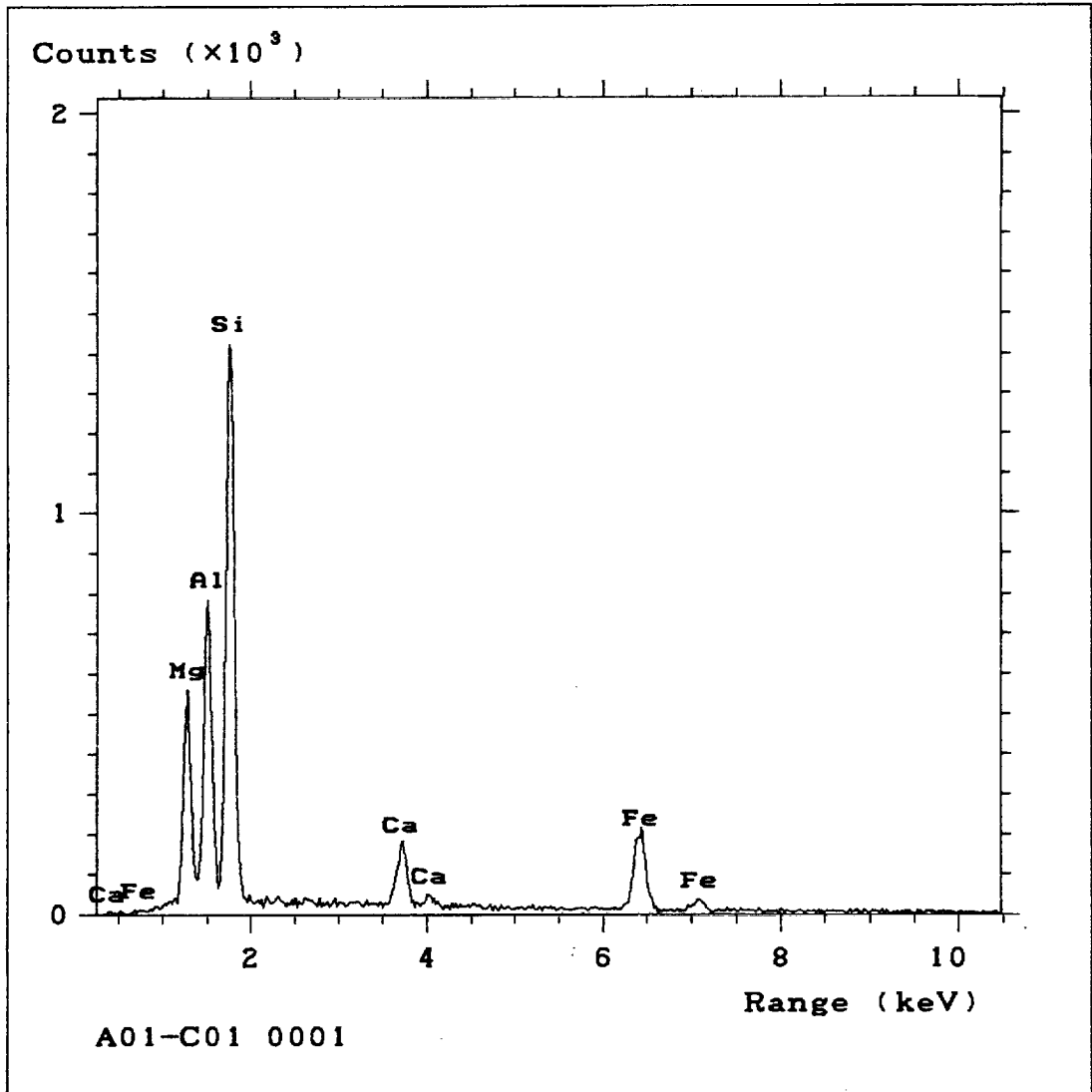
FIGURE 9. Histogram illustrating the determined impactor type versus the impact crater diameter. Samples listed as being contaminated contain significant amounts of foreign material and projectile remnants that are not easily identified.

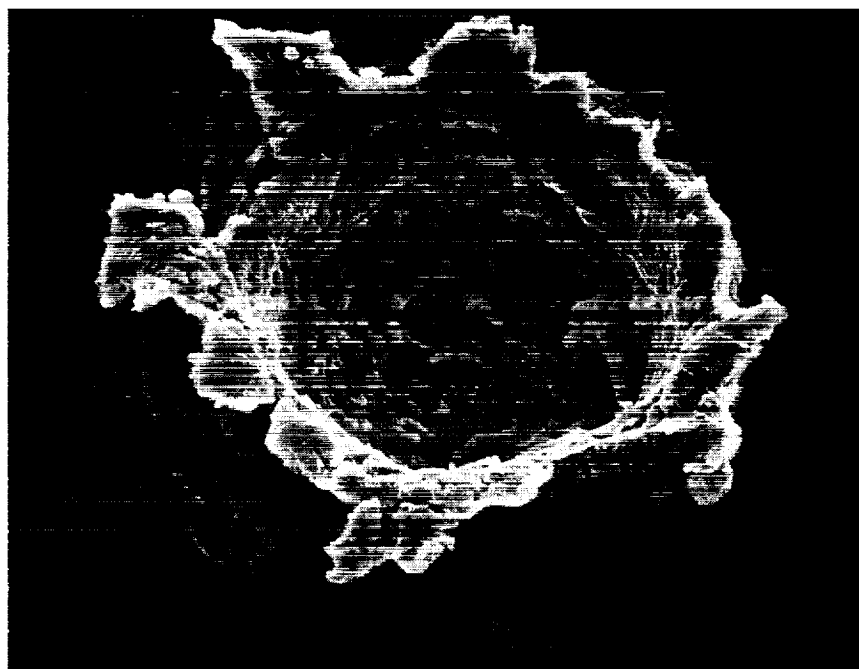
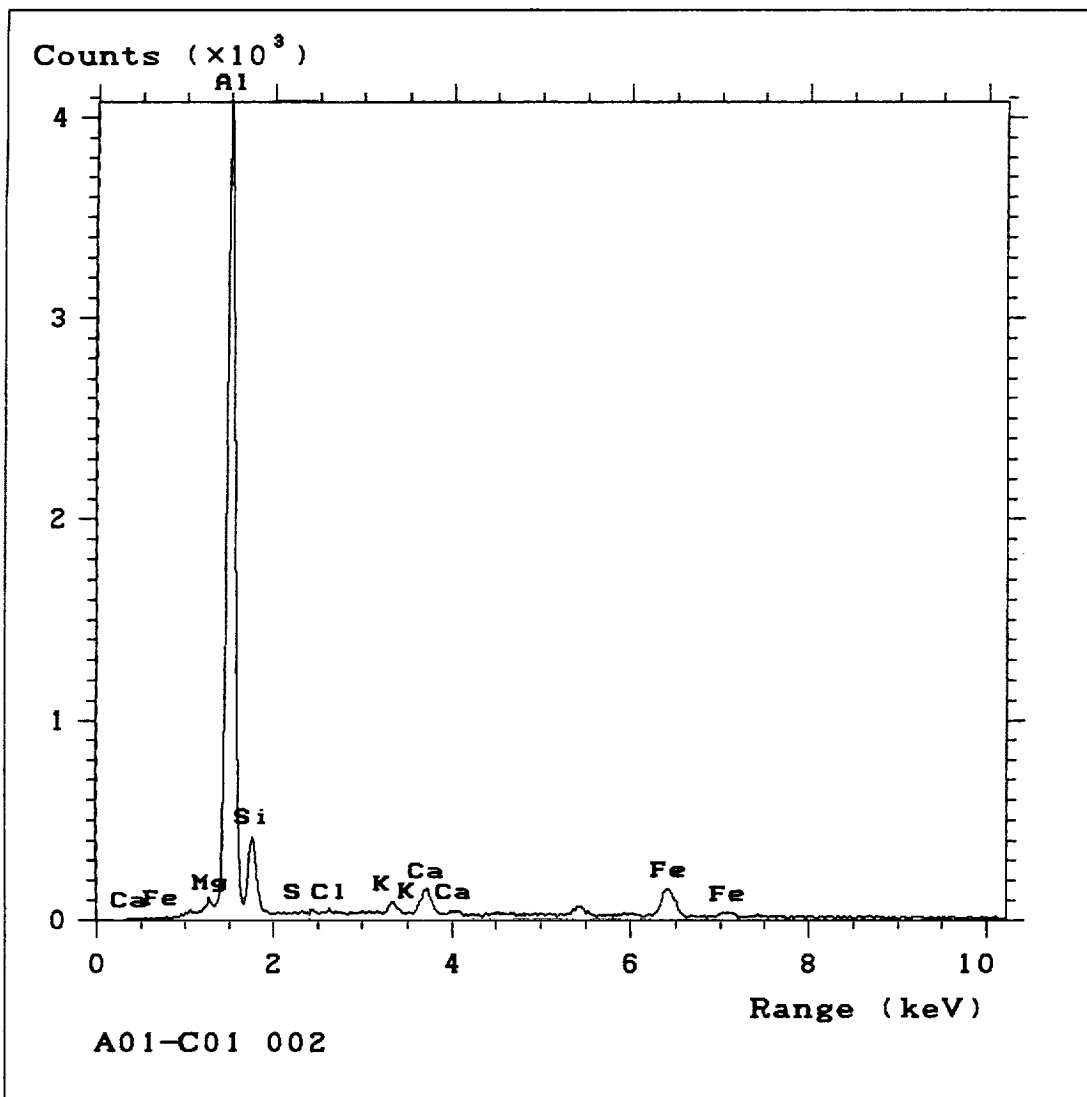
Appendix A

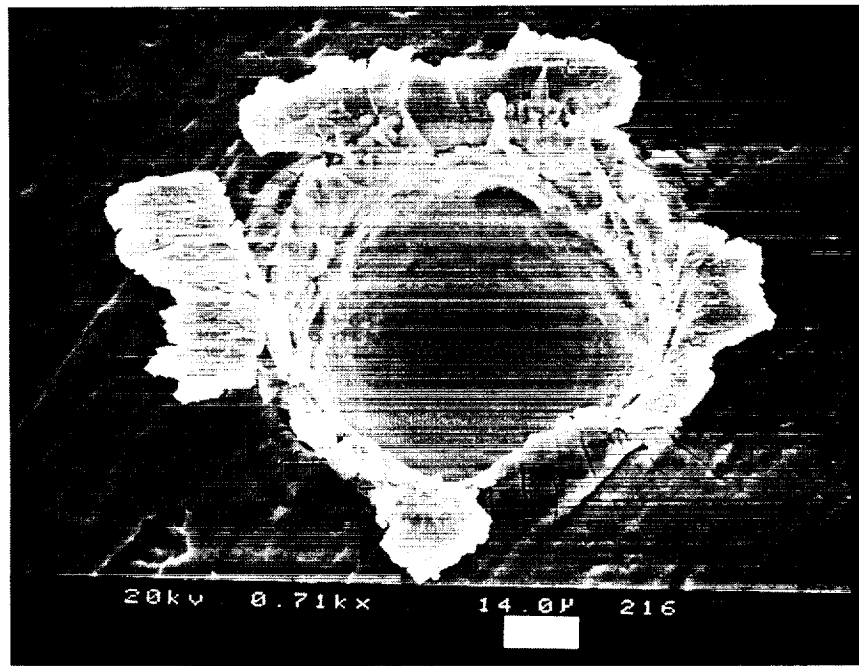
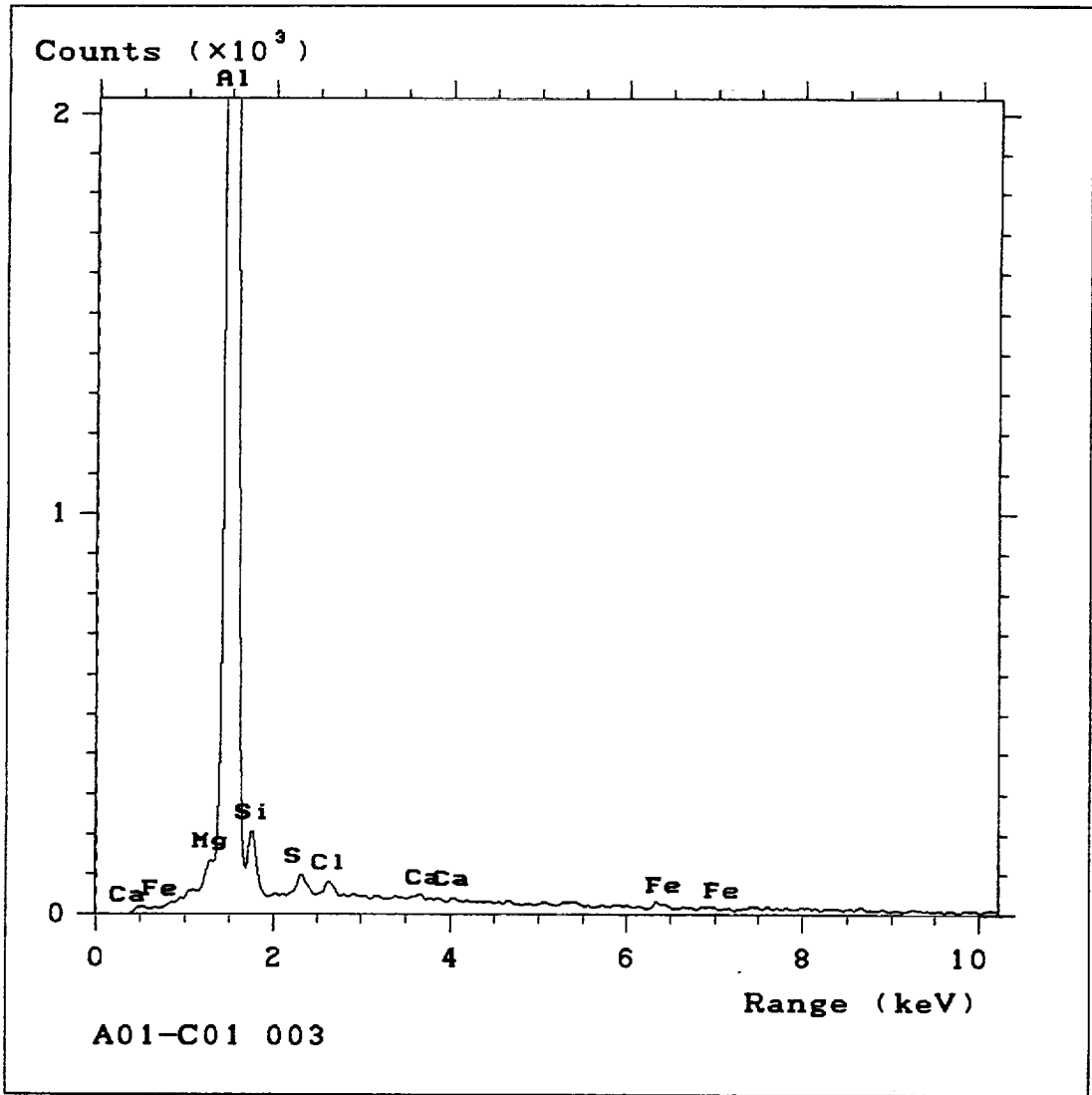
CLAMP NUMBER A01 C01

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	200	Mg, Si, Ca, Fe
002	100	Trace
003	100	Unkown



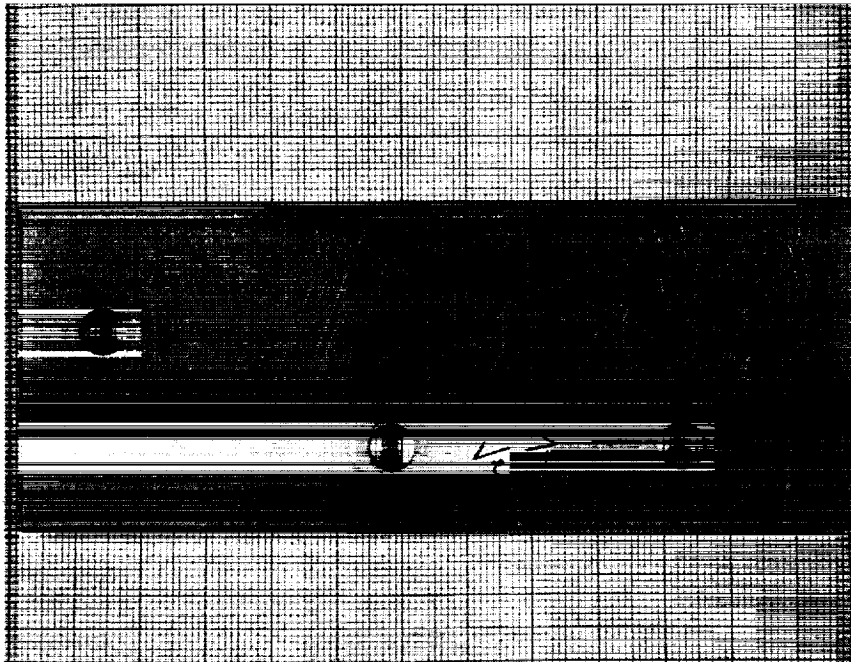


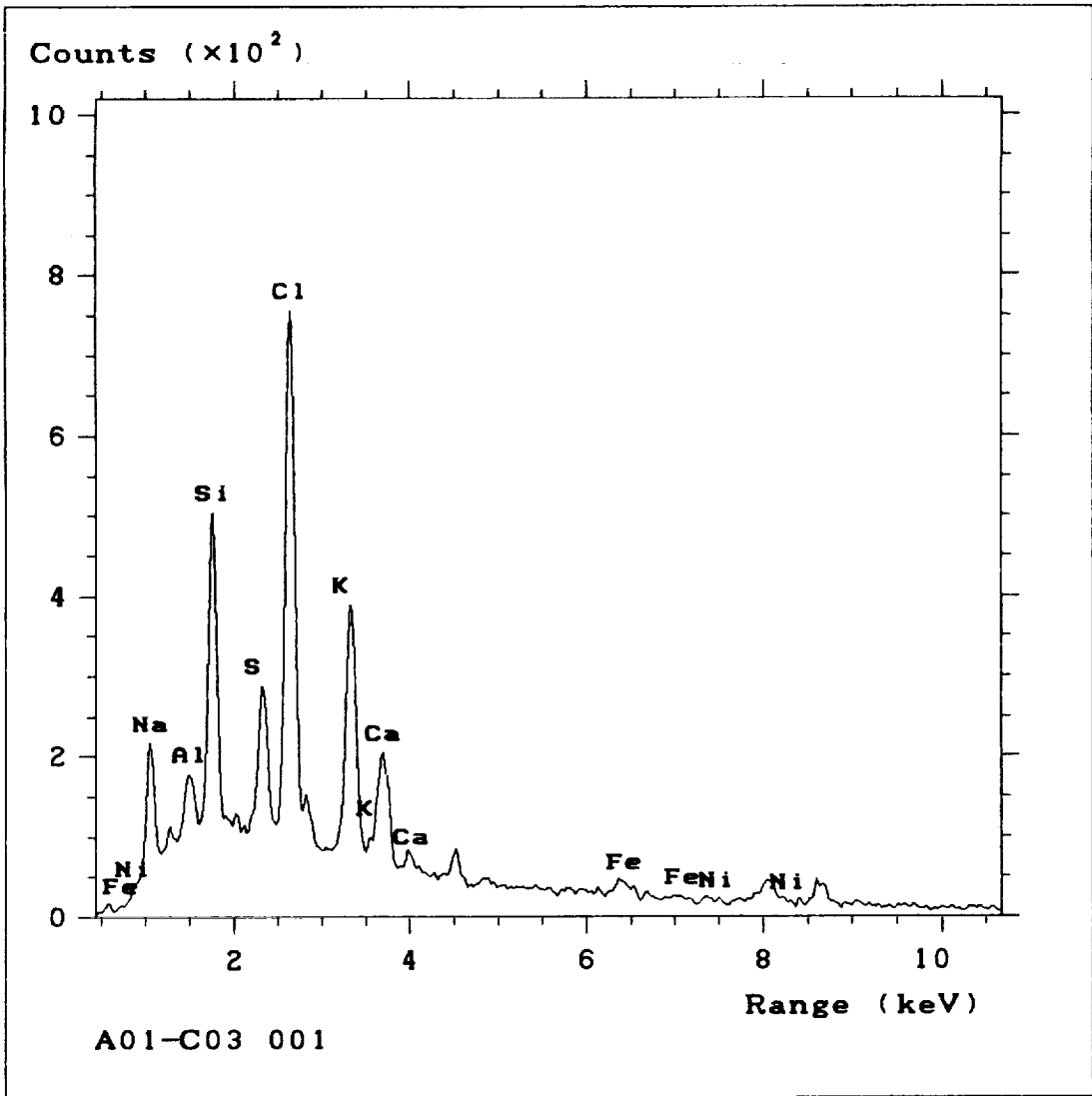


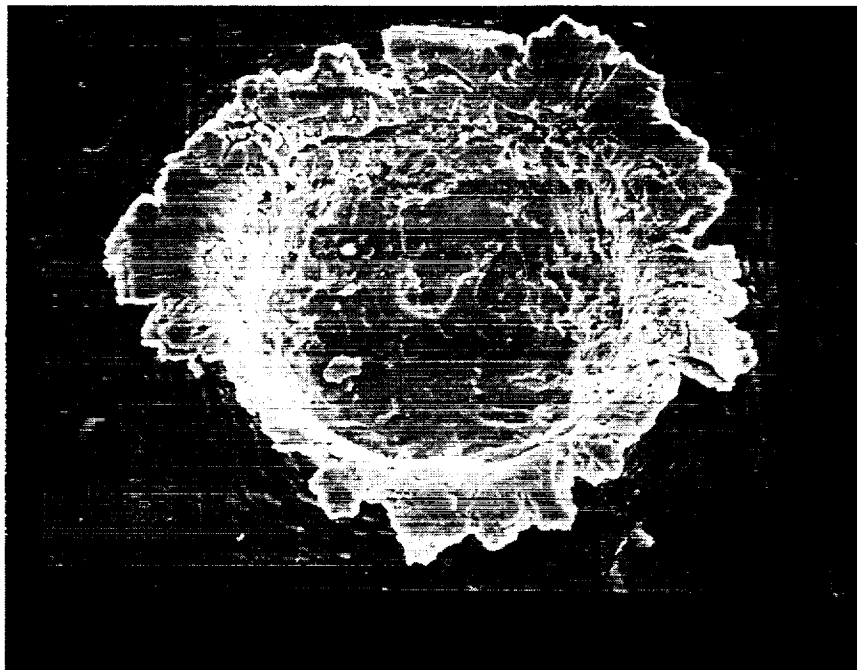
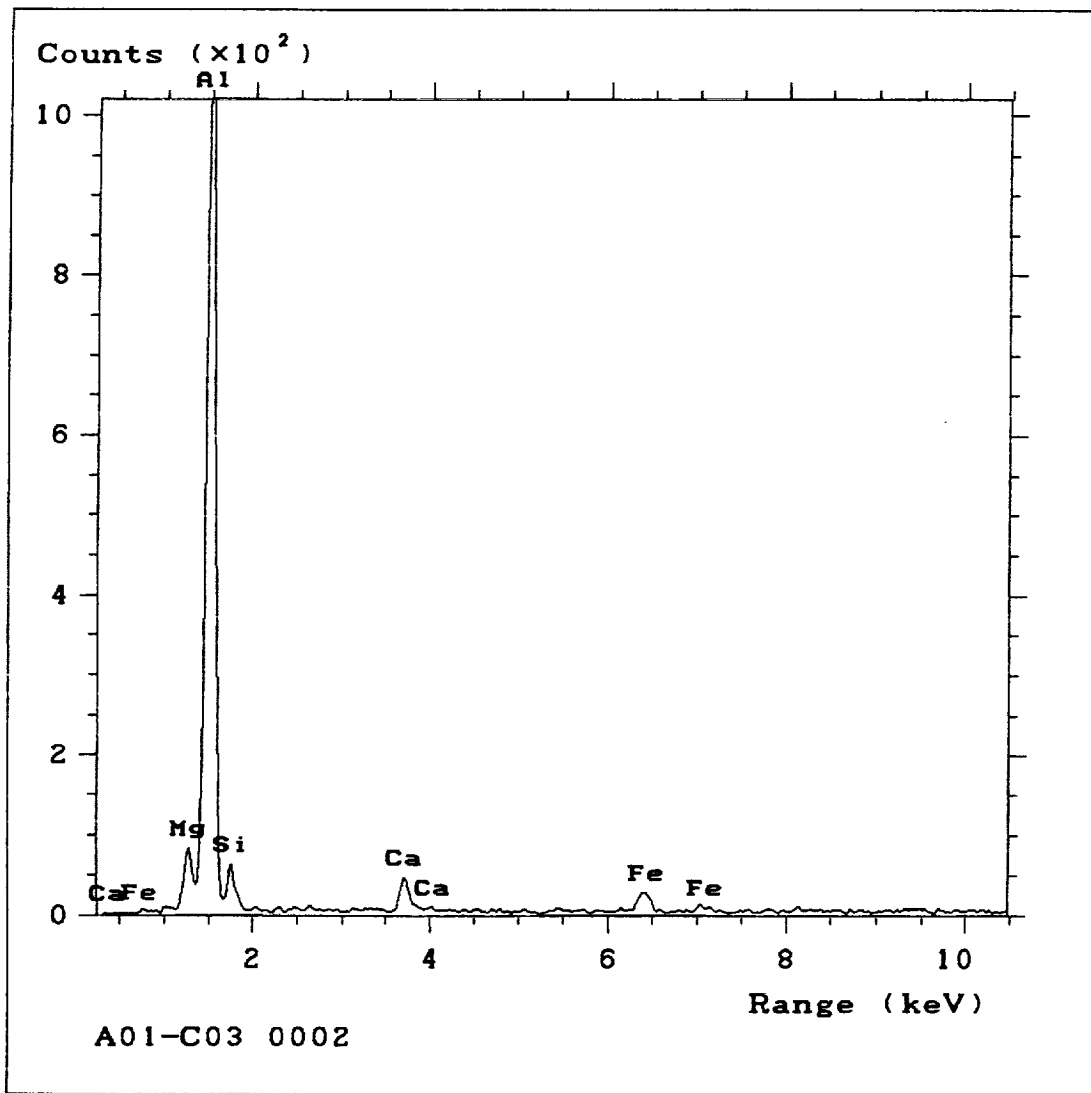


CLAMP NUMBER A01 CO3

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	120	Contamination
002	230	Mg, Si, Ca, Fe

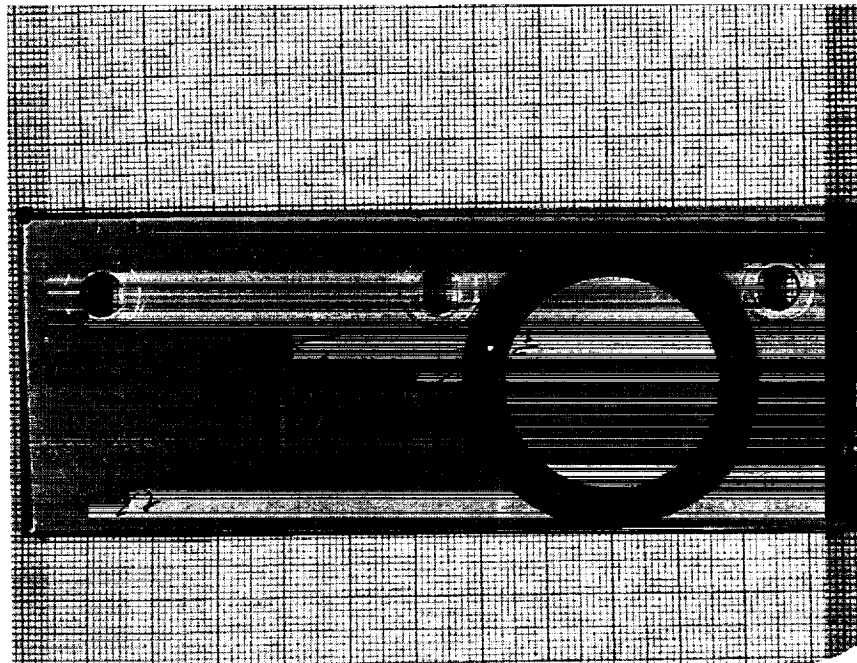


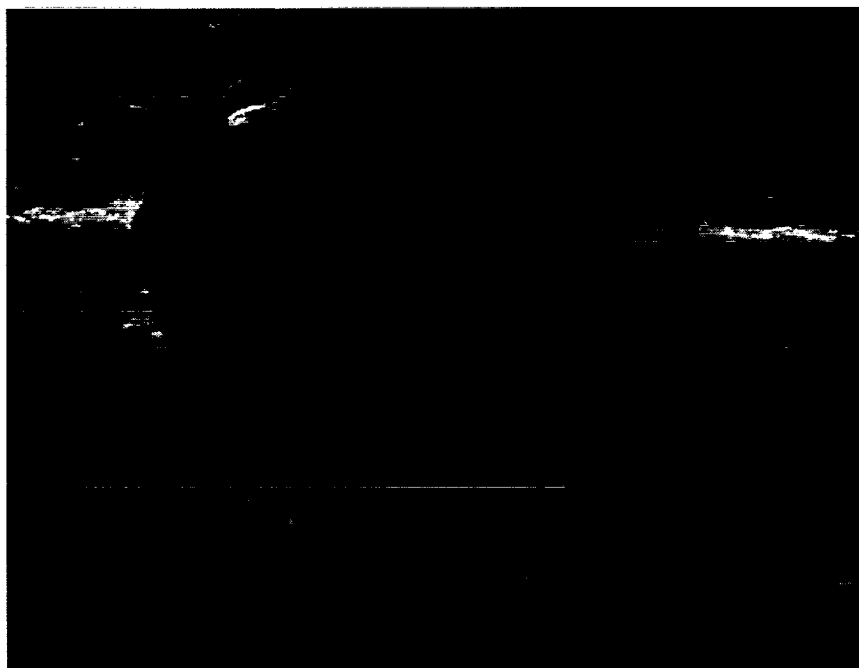
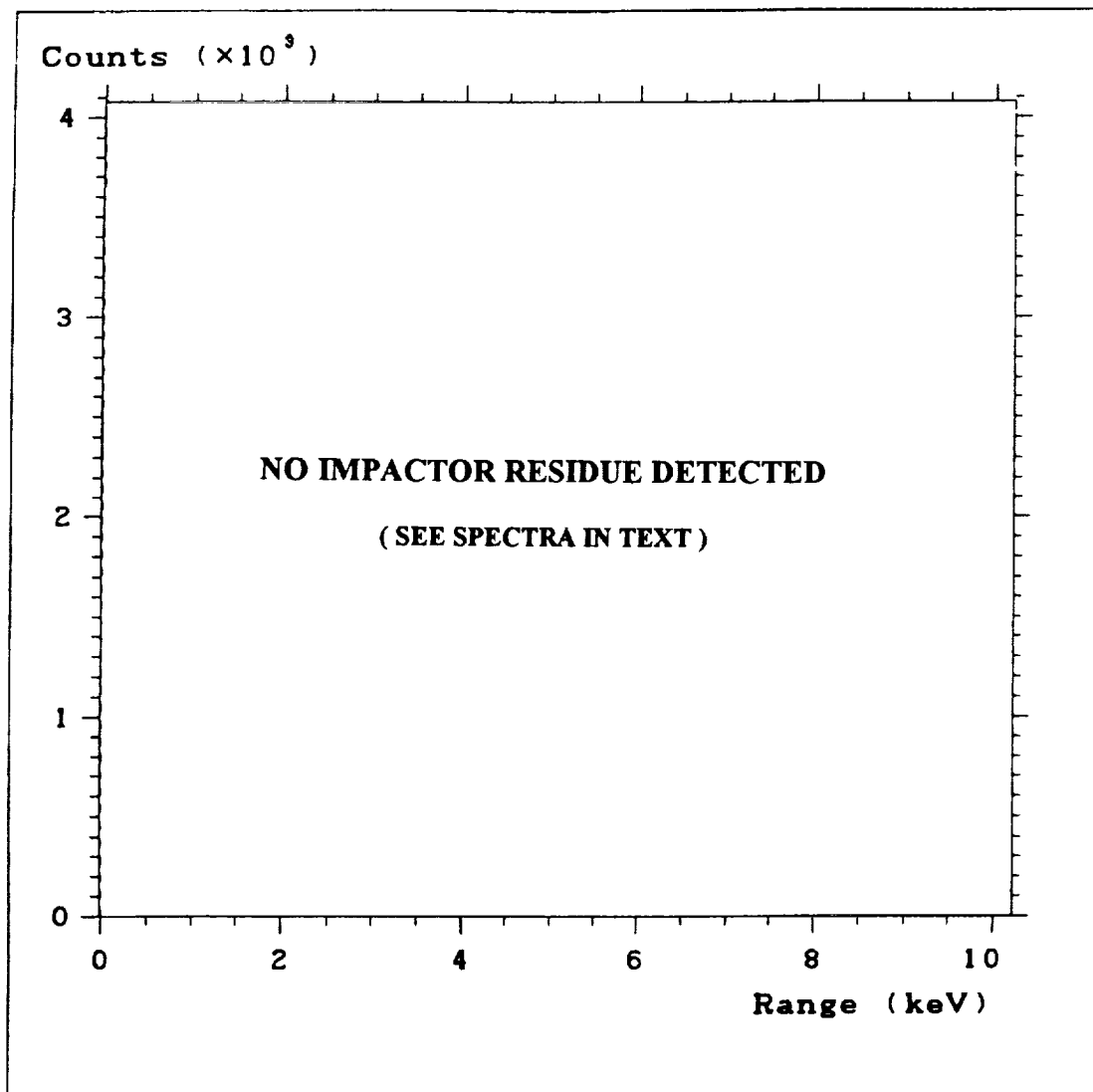


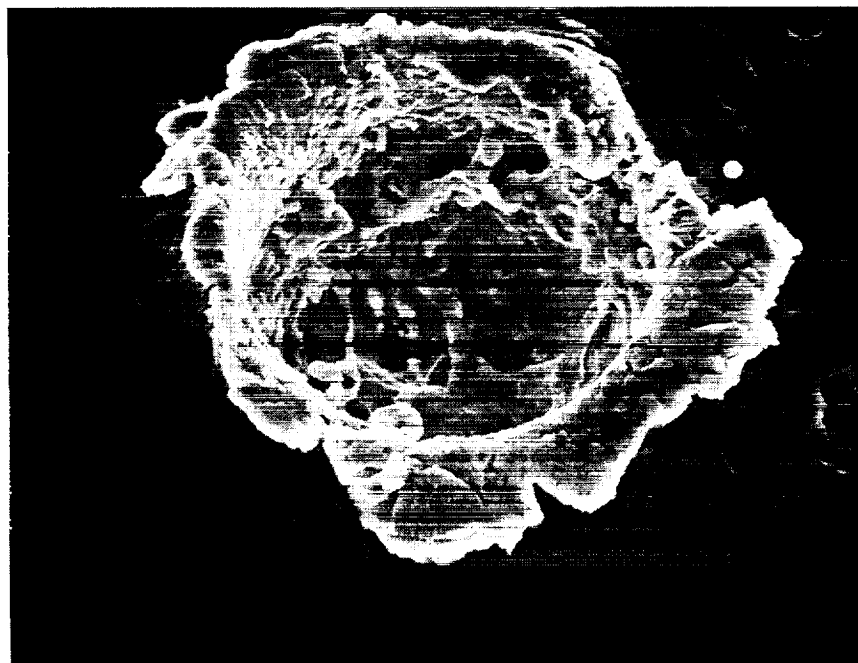
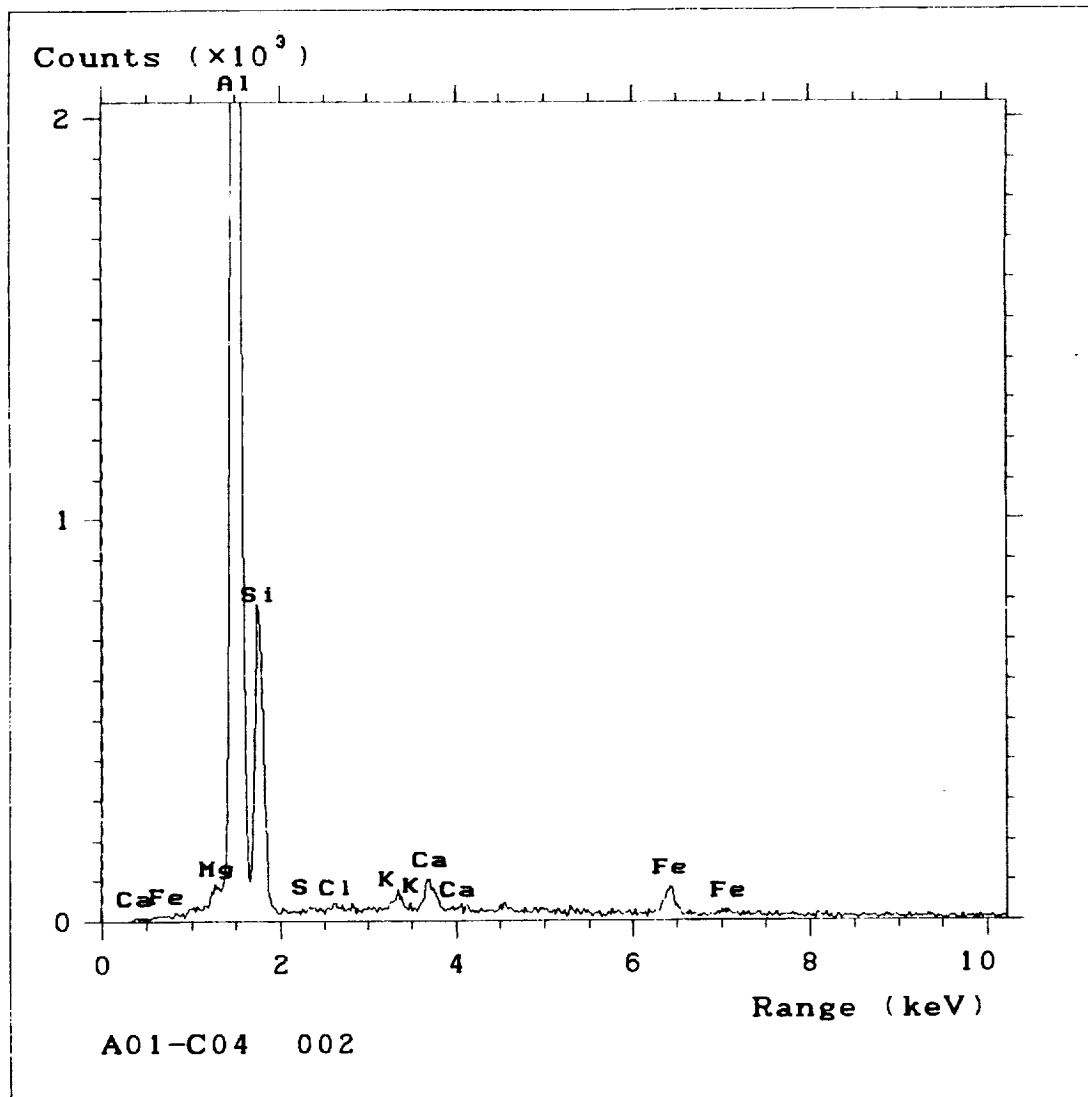


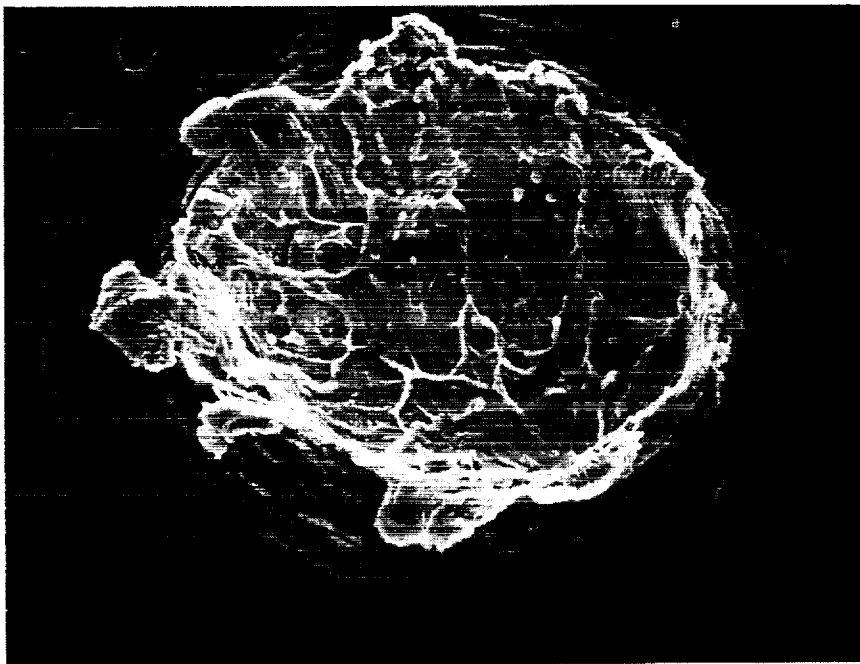
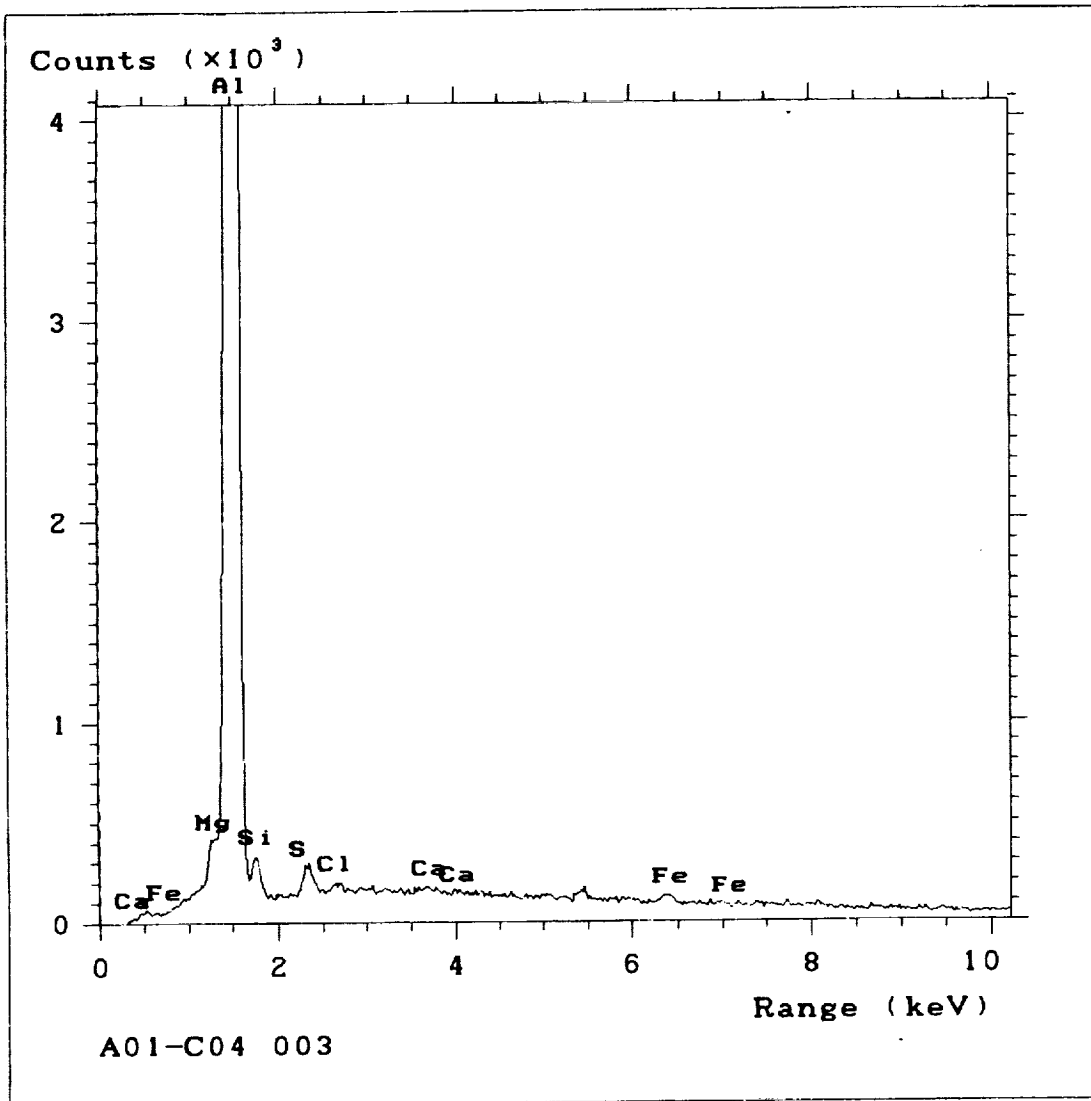
CLAMP NUMBER A01 C04

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	100	Paint Patch
002	180	Trace
003	140	Unknown



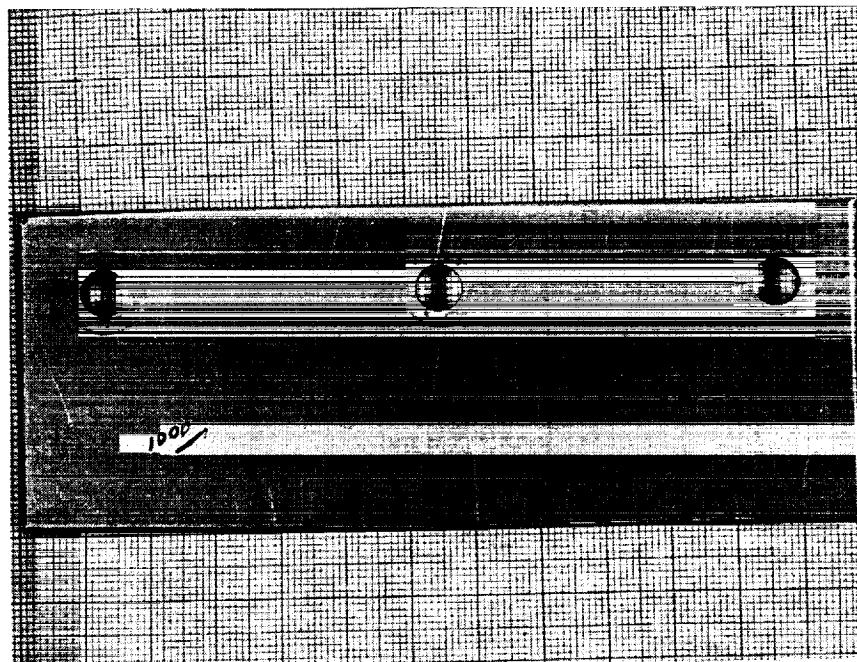


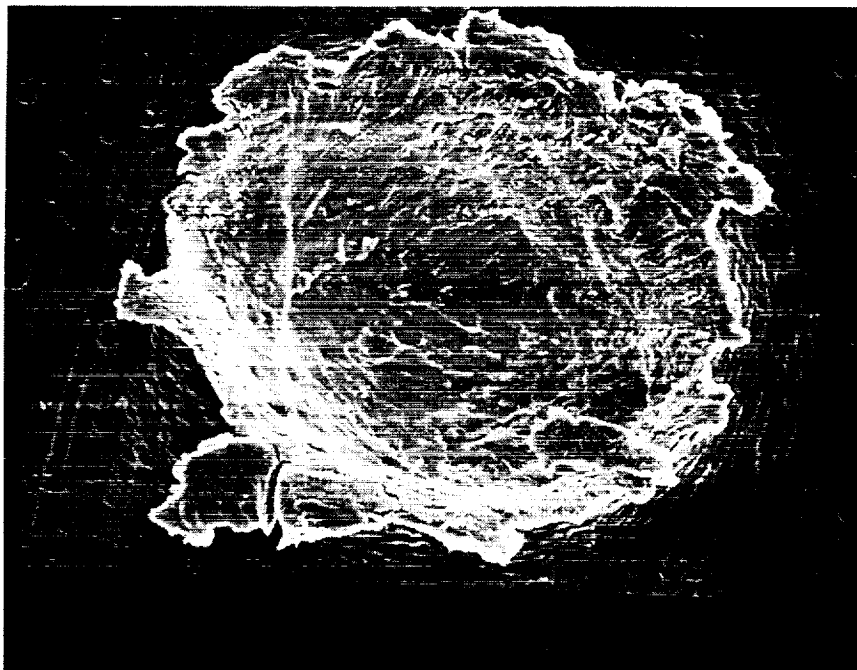
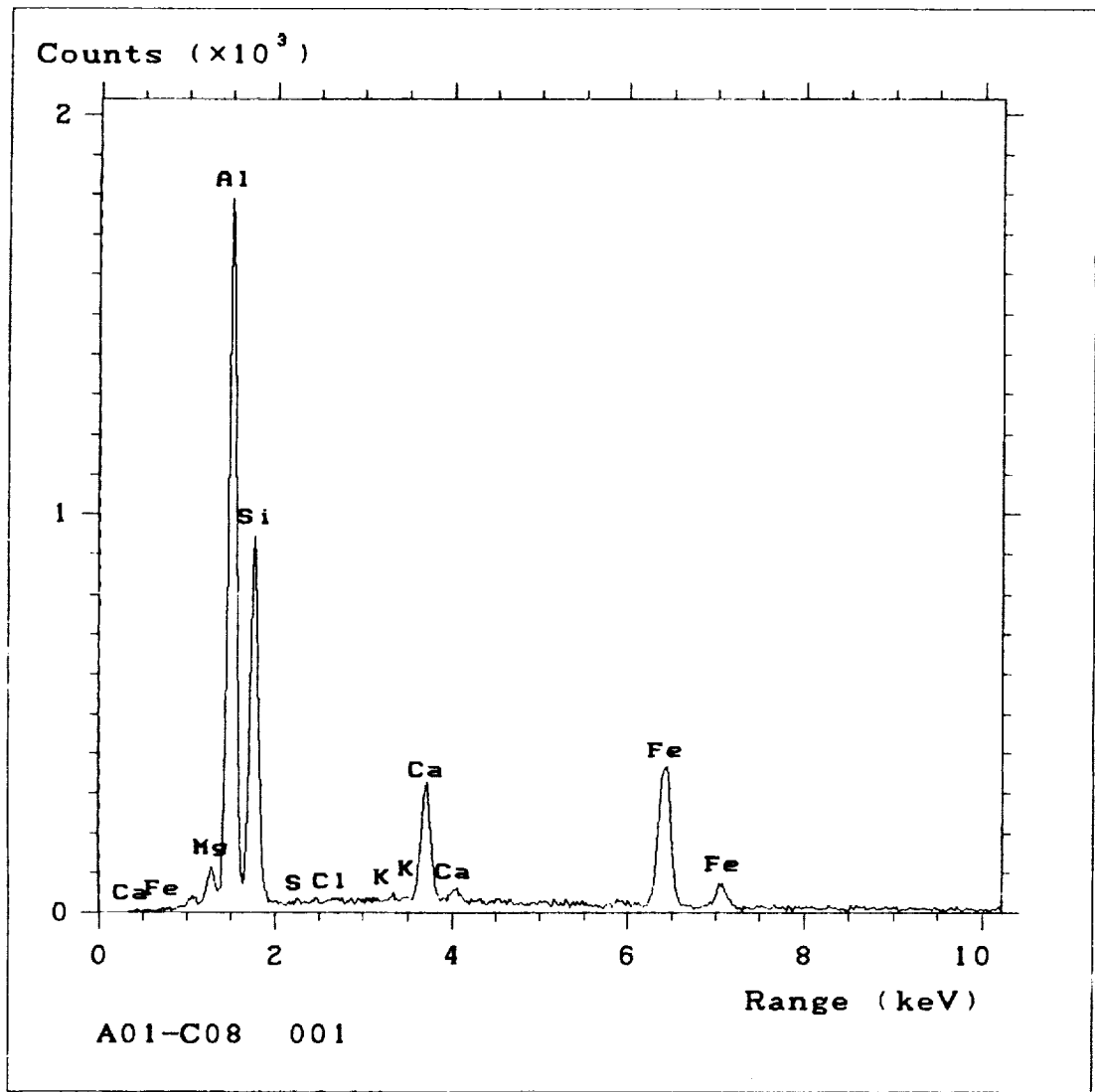




CLAMP NUMBER A01 CO8

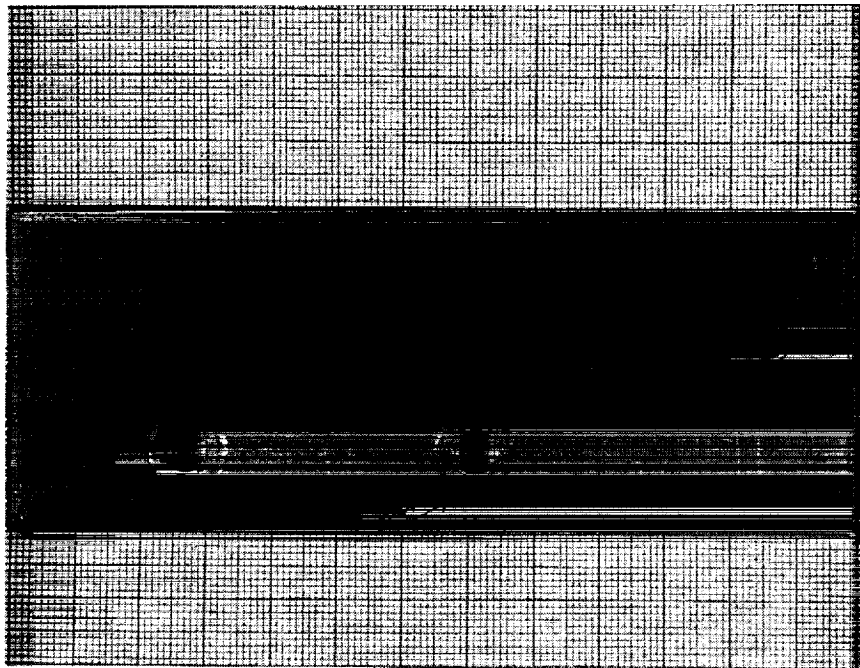
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	370	Mg, Si, Ca, Fe

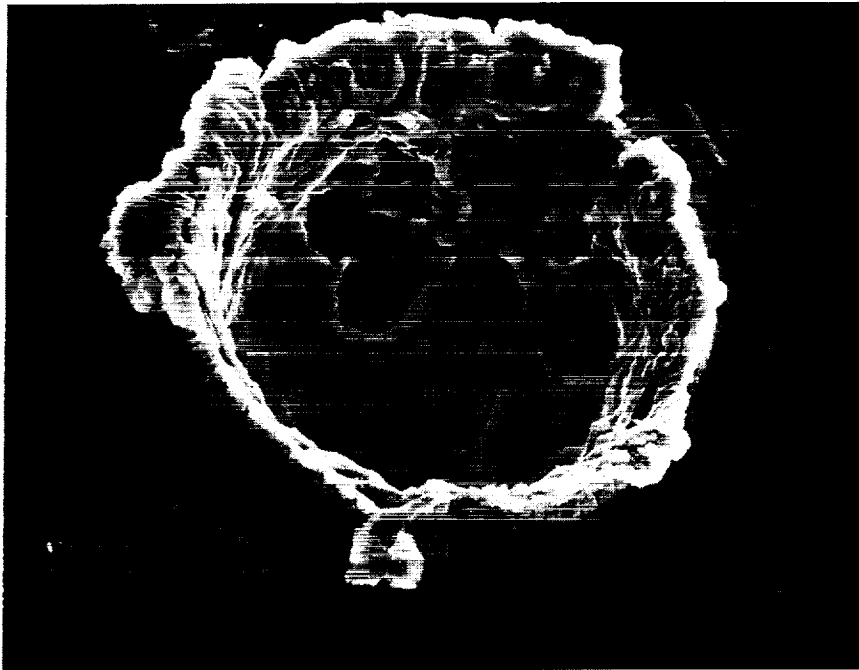
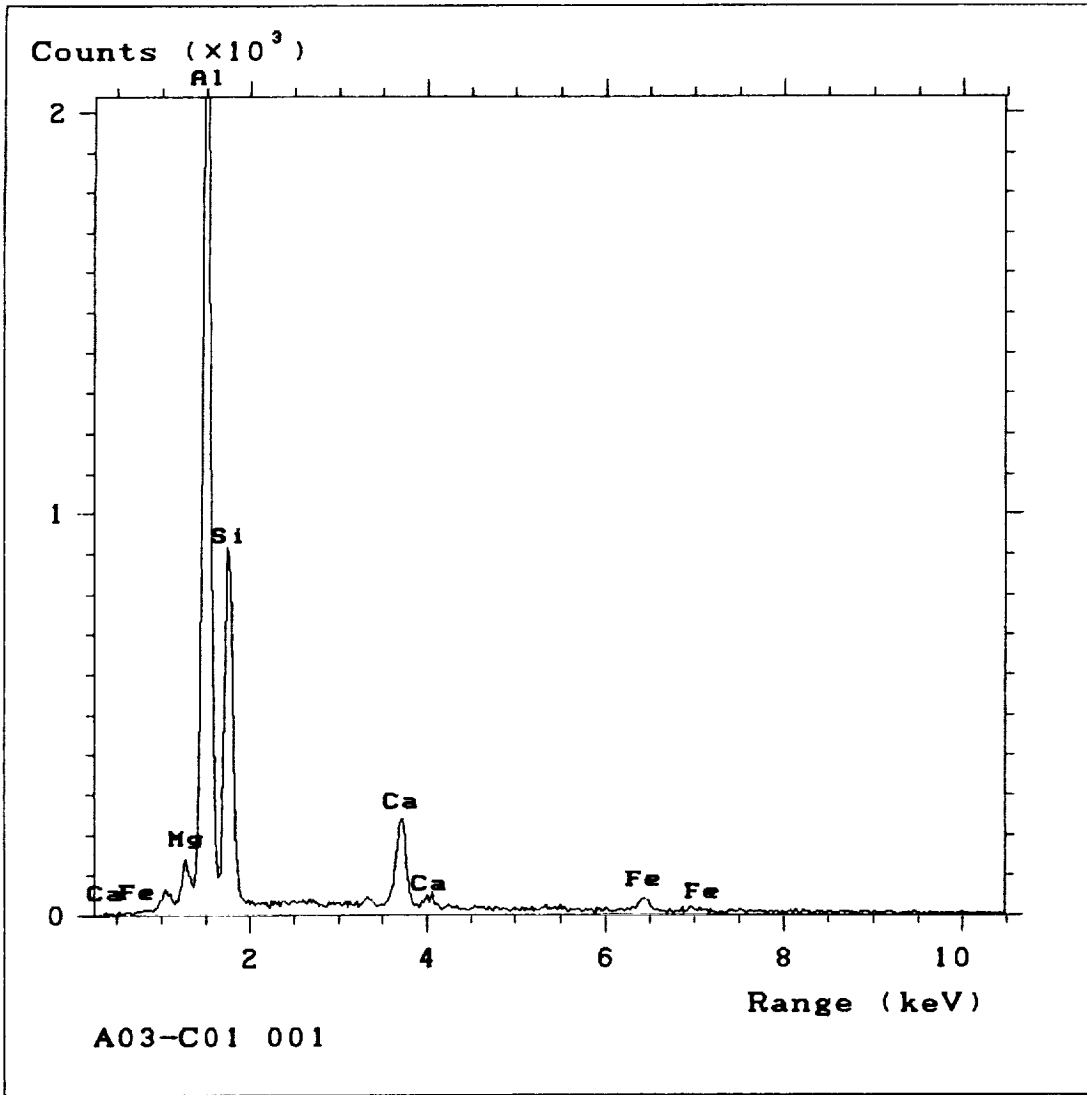




CLAMP NUMBER A03 CO1

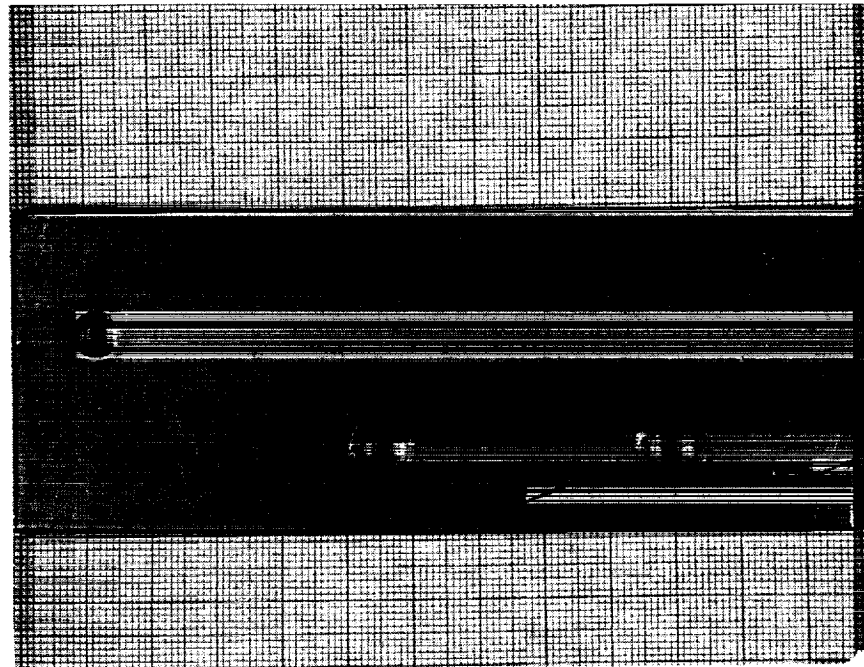
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	150	Mg, Si, Ca, Fe

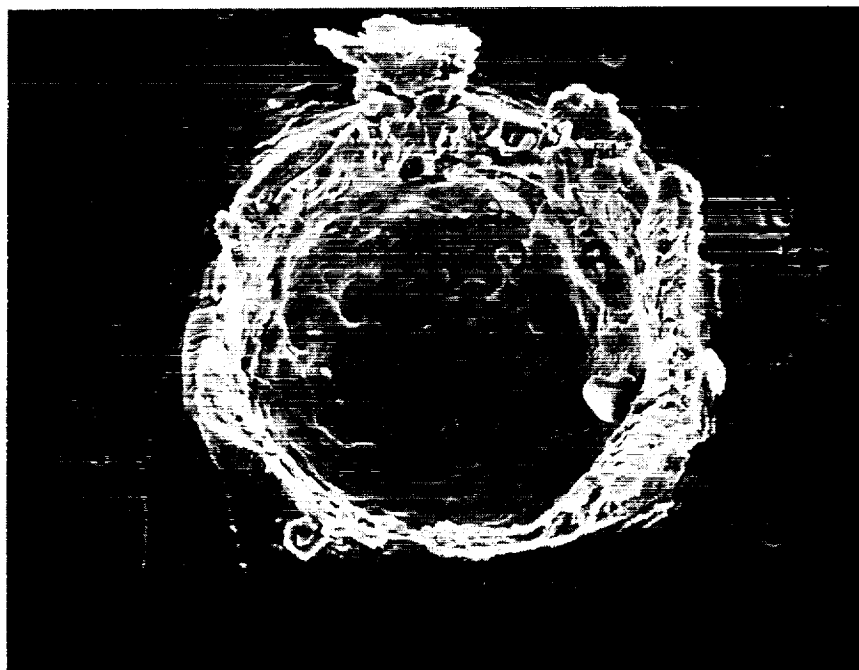
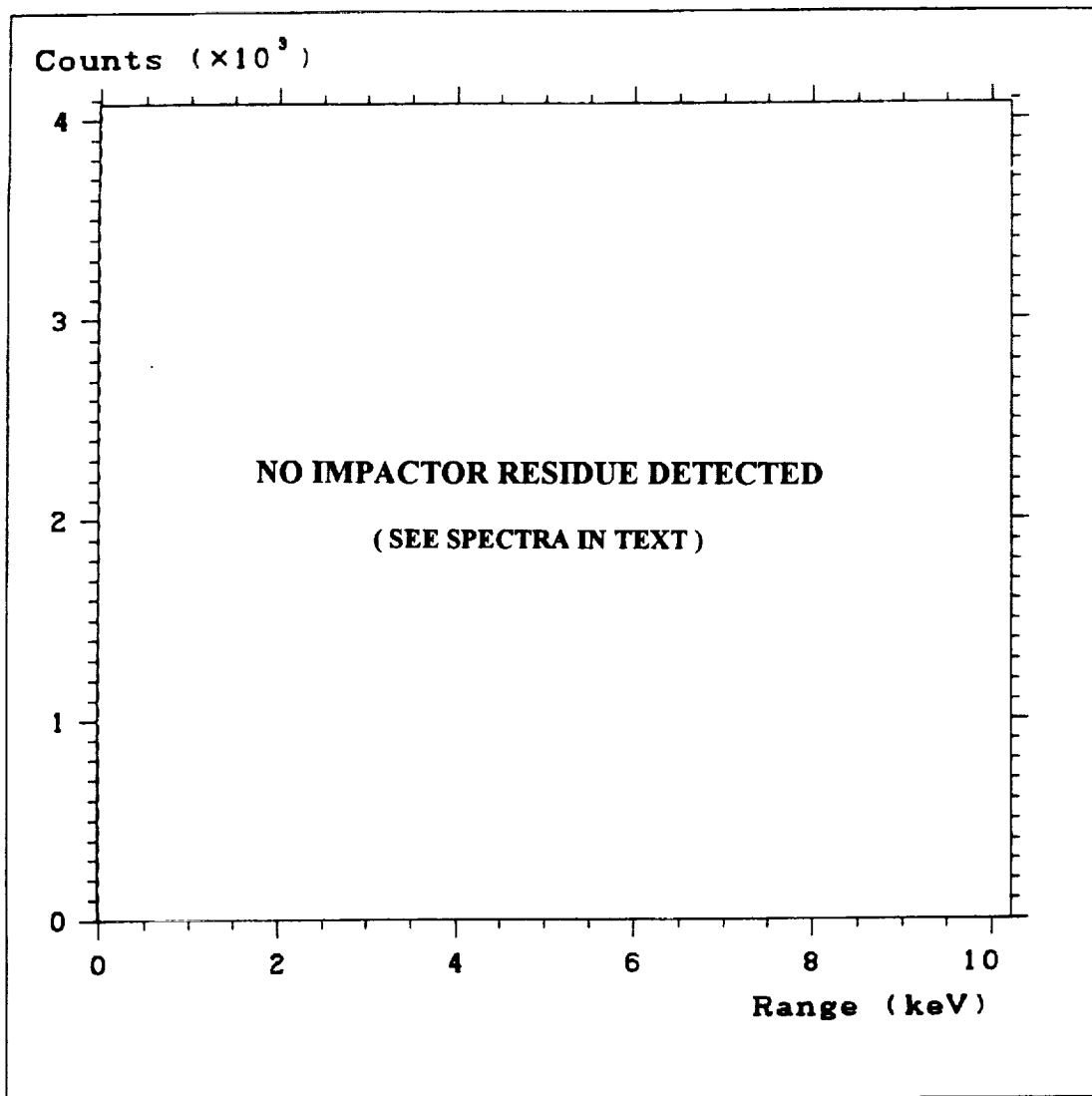




CLAMP NUMBER A03 C03

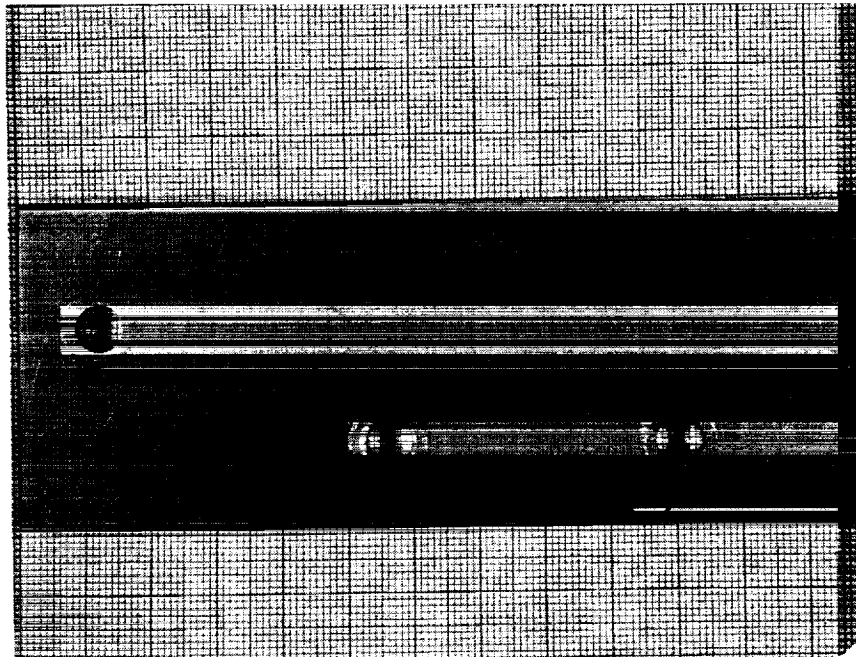
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	220	Unkown

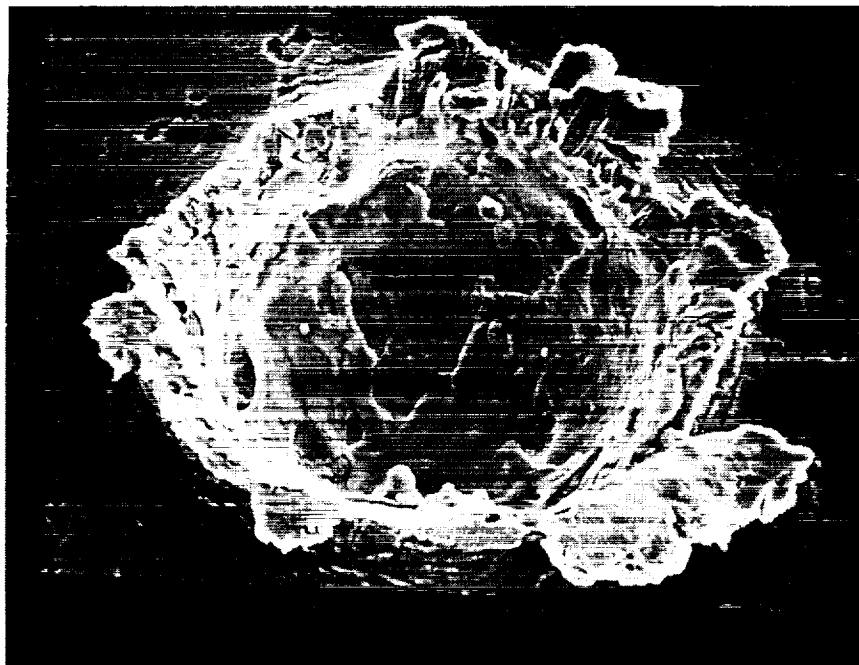
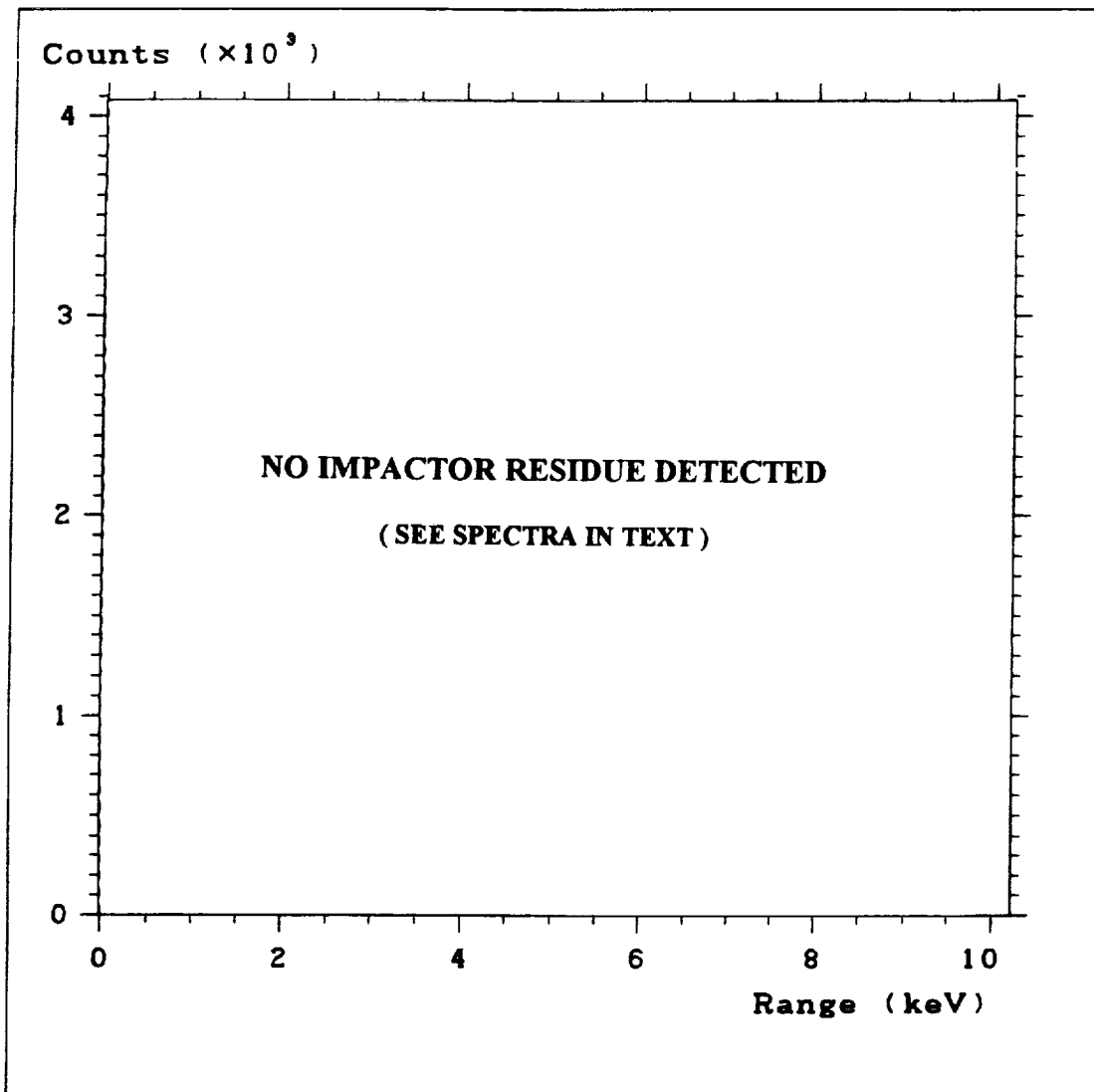




CLAMP NUMBER A04 C03

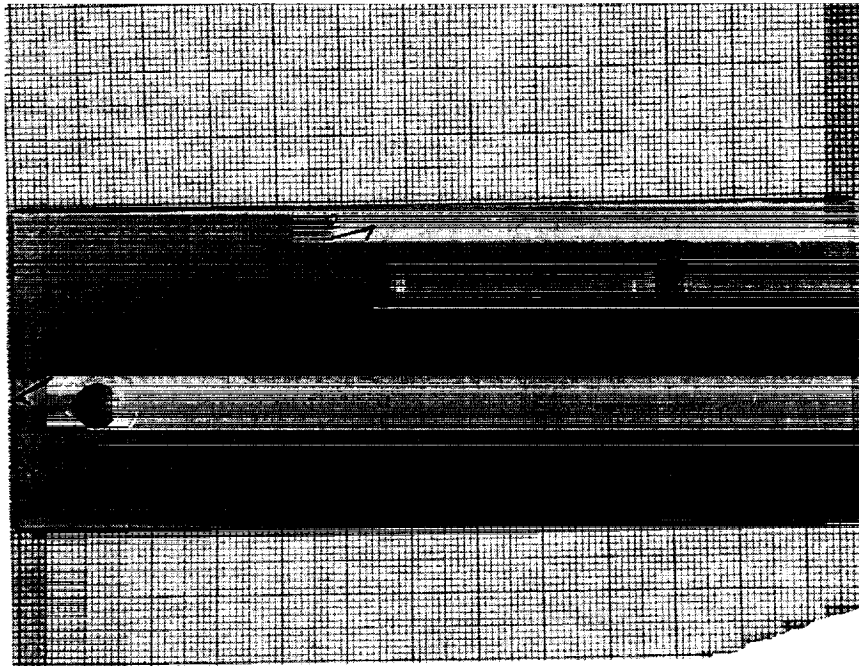
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	260	Unkown

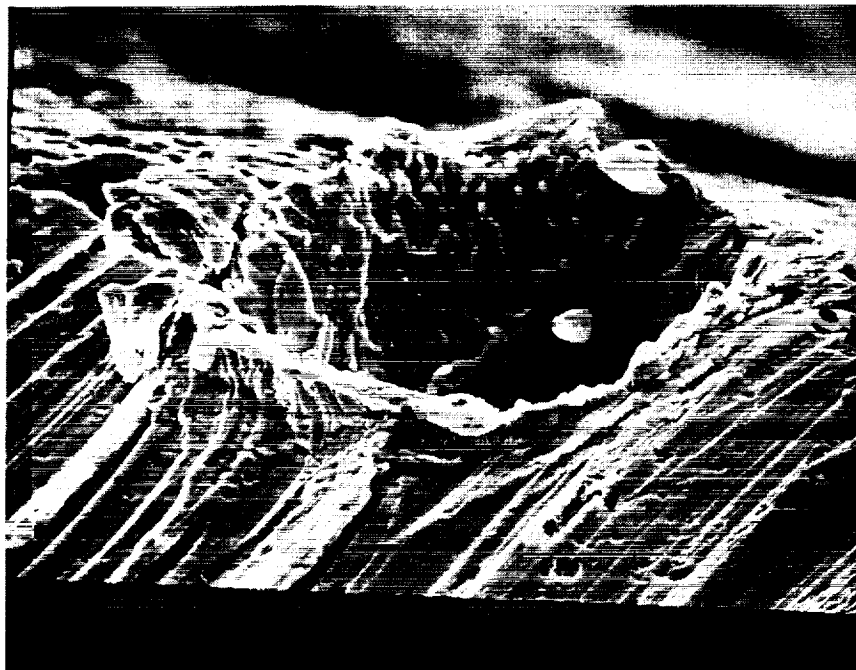
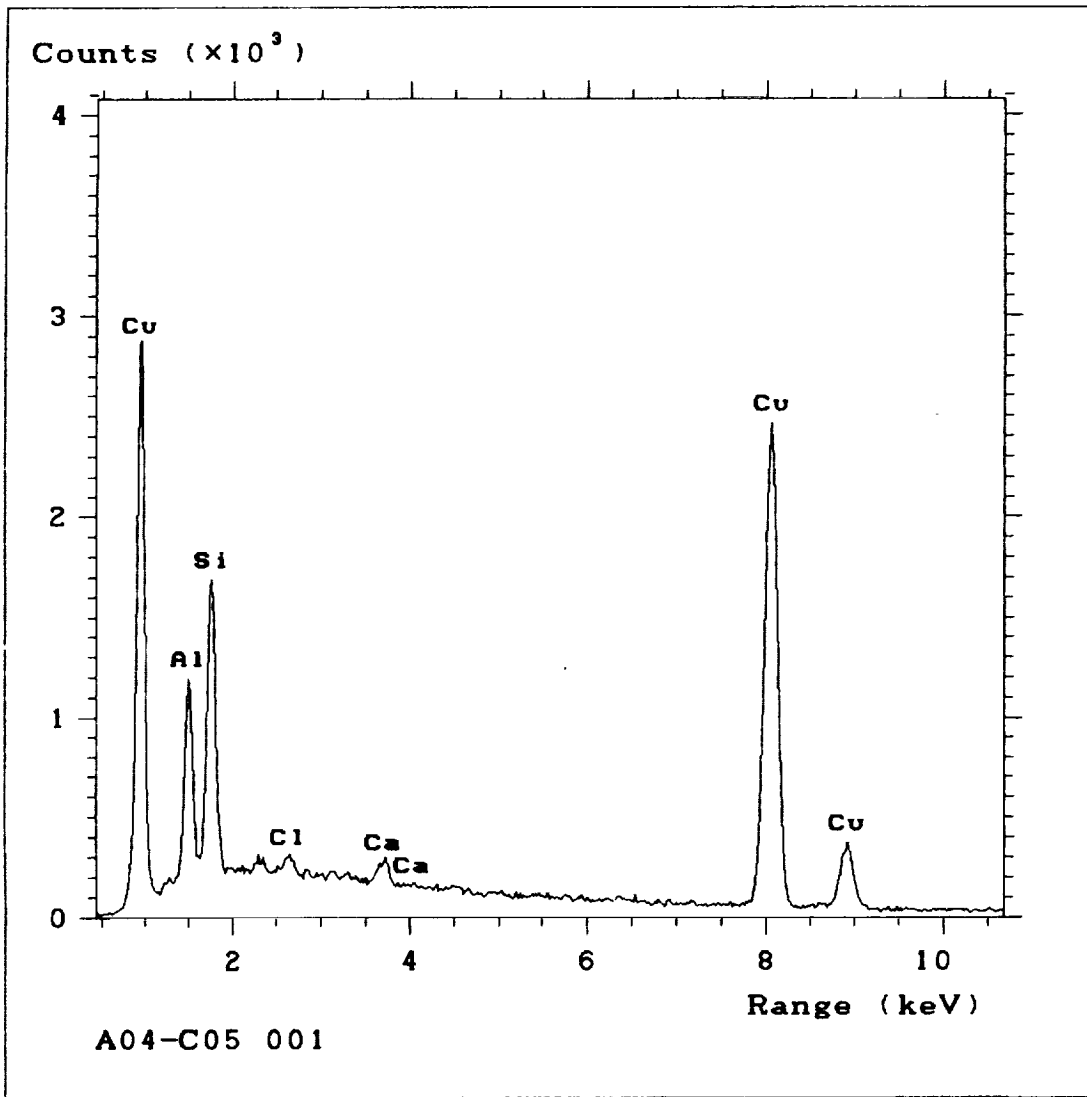


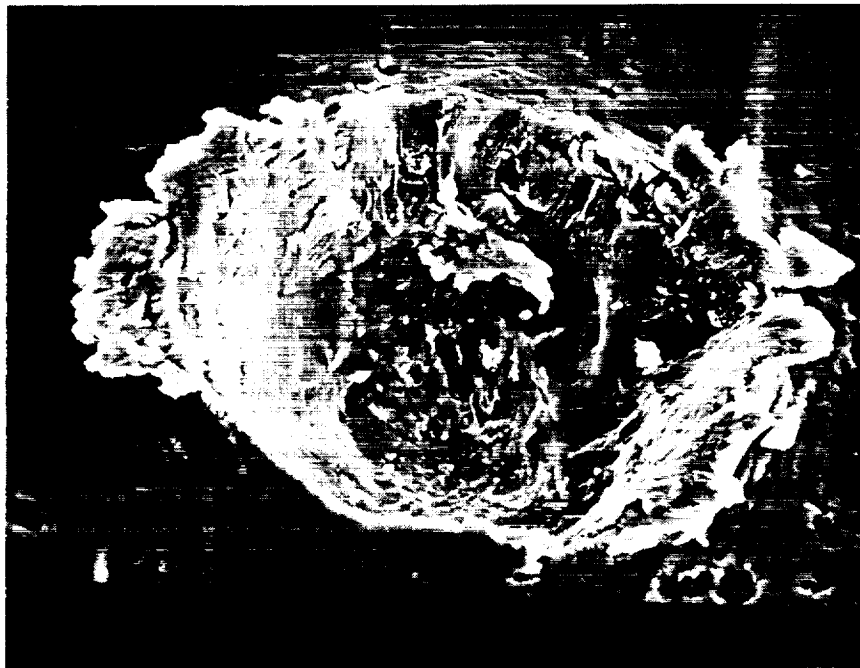
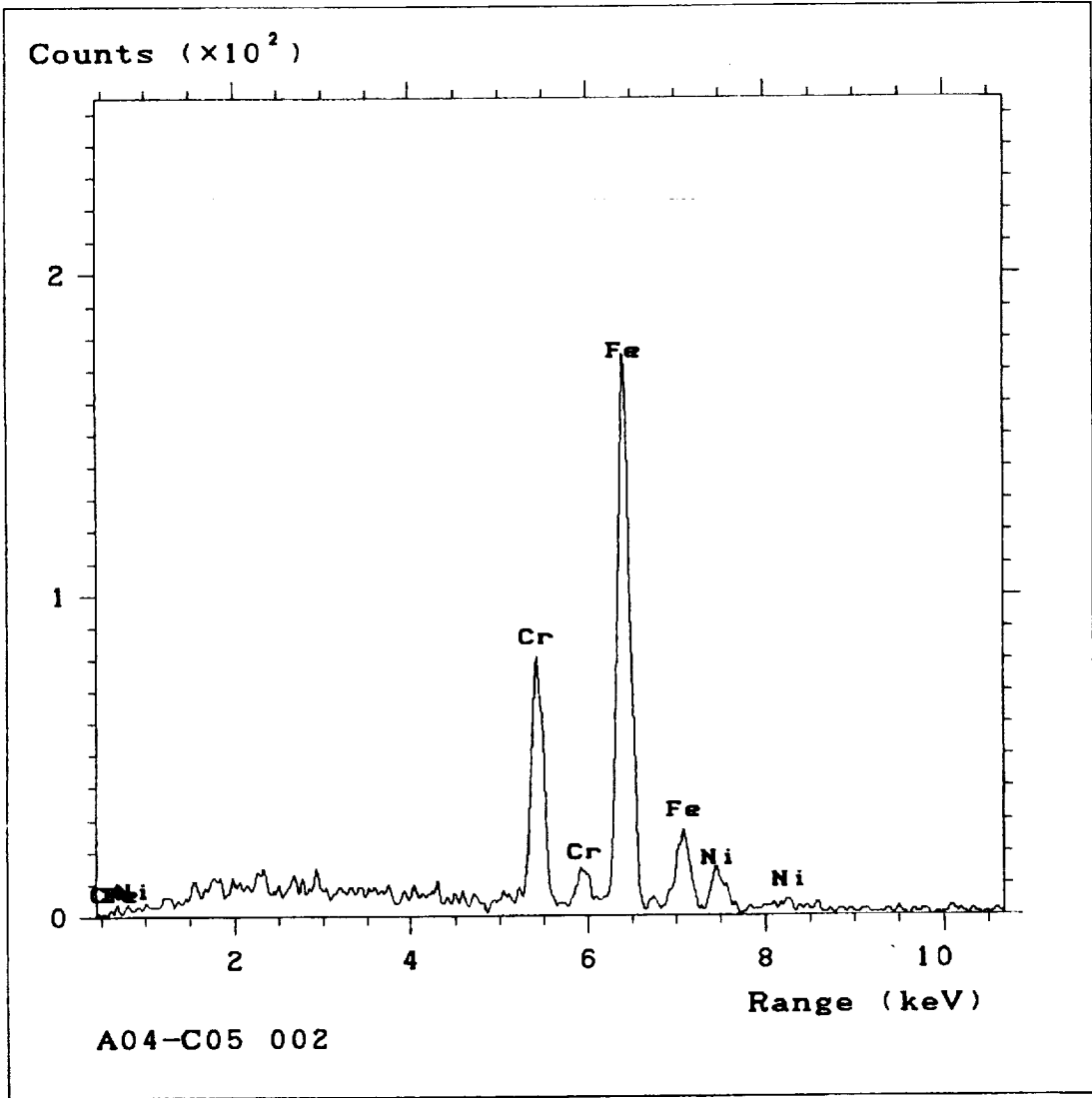


CLAMP NUMBER A04 C05

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	210	Contamination
002	120	Fe, Ni, Cr

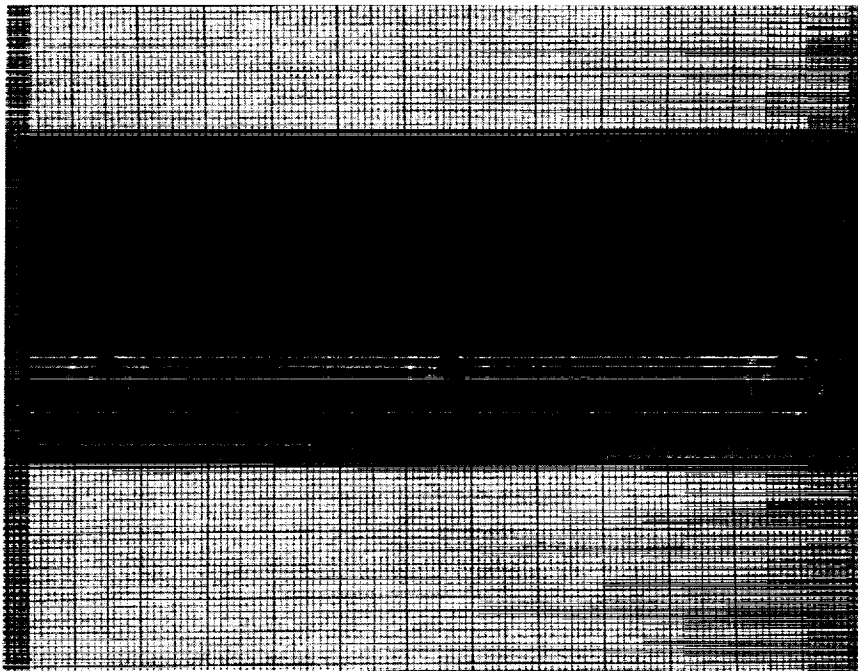


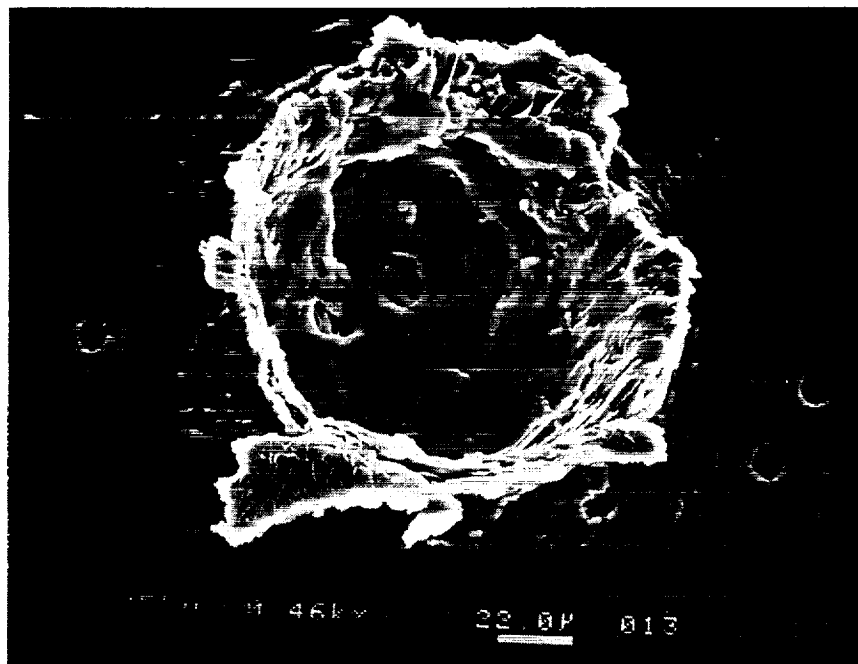
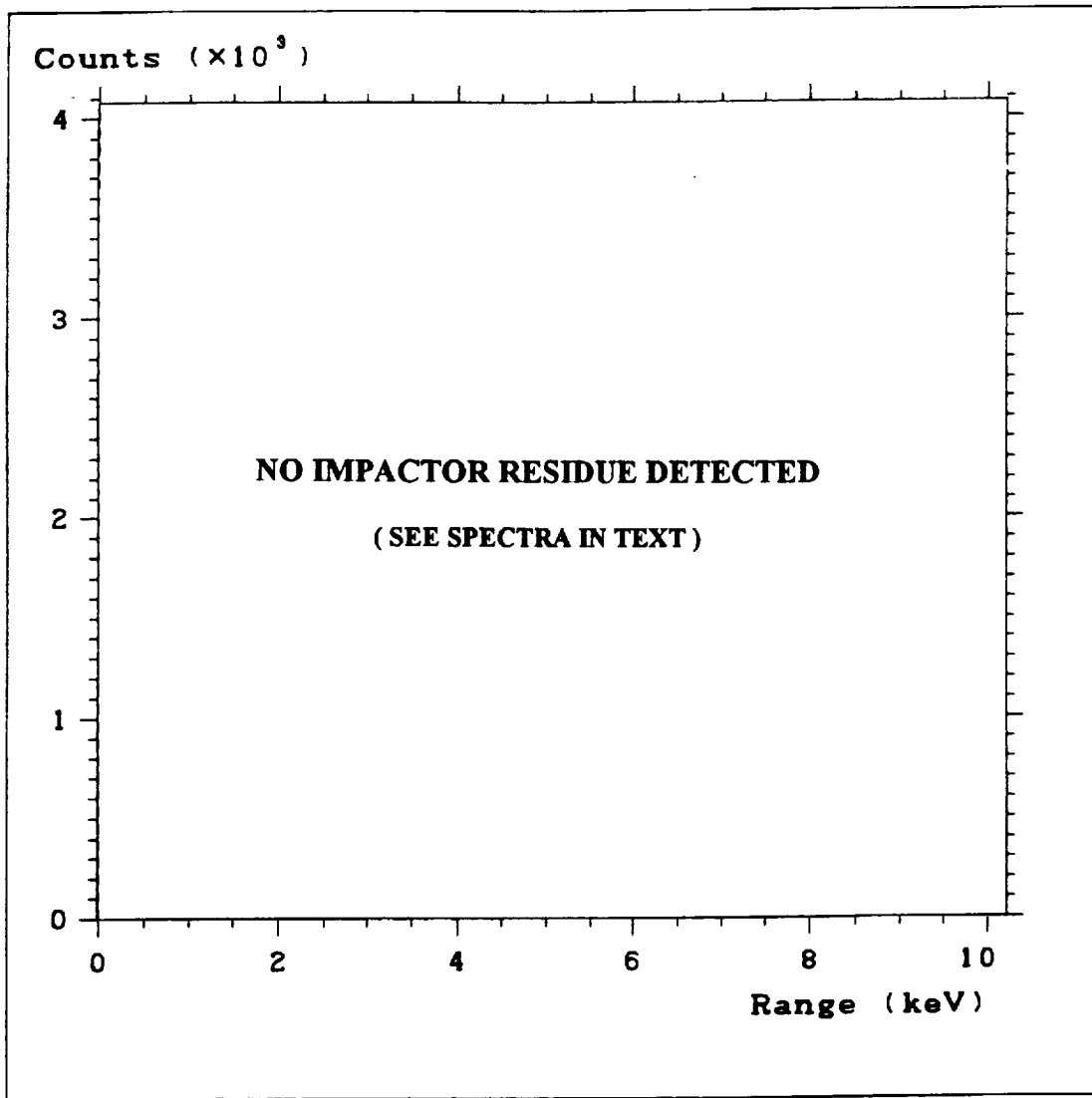


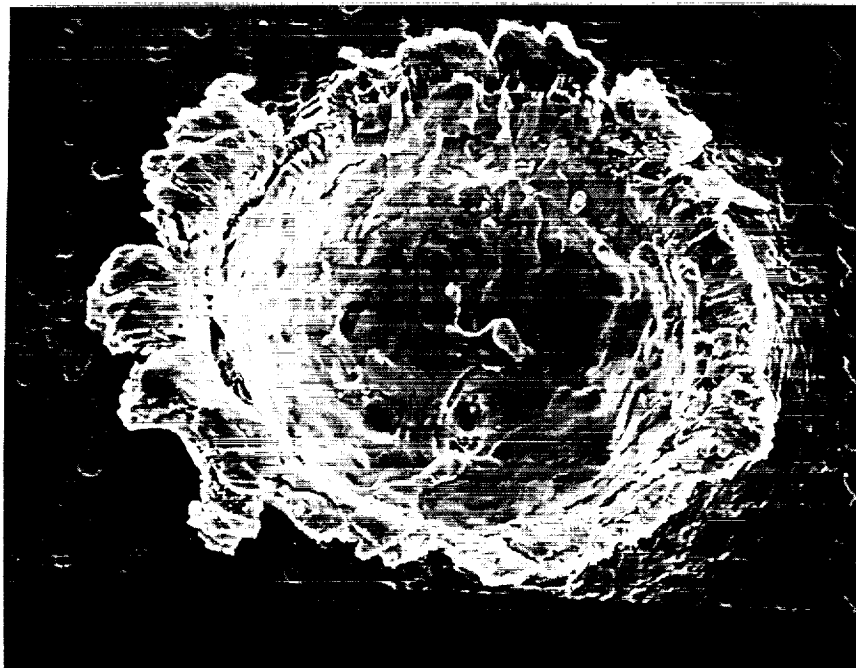
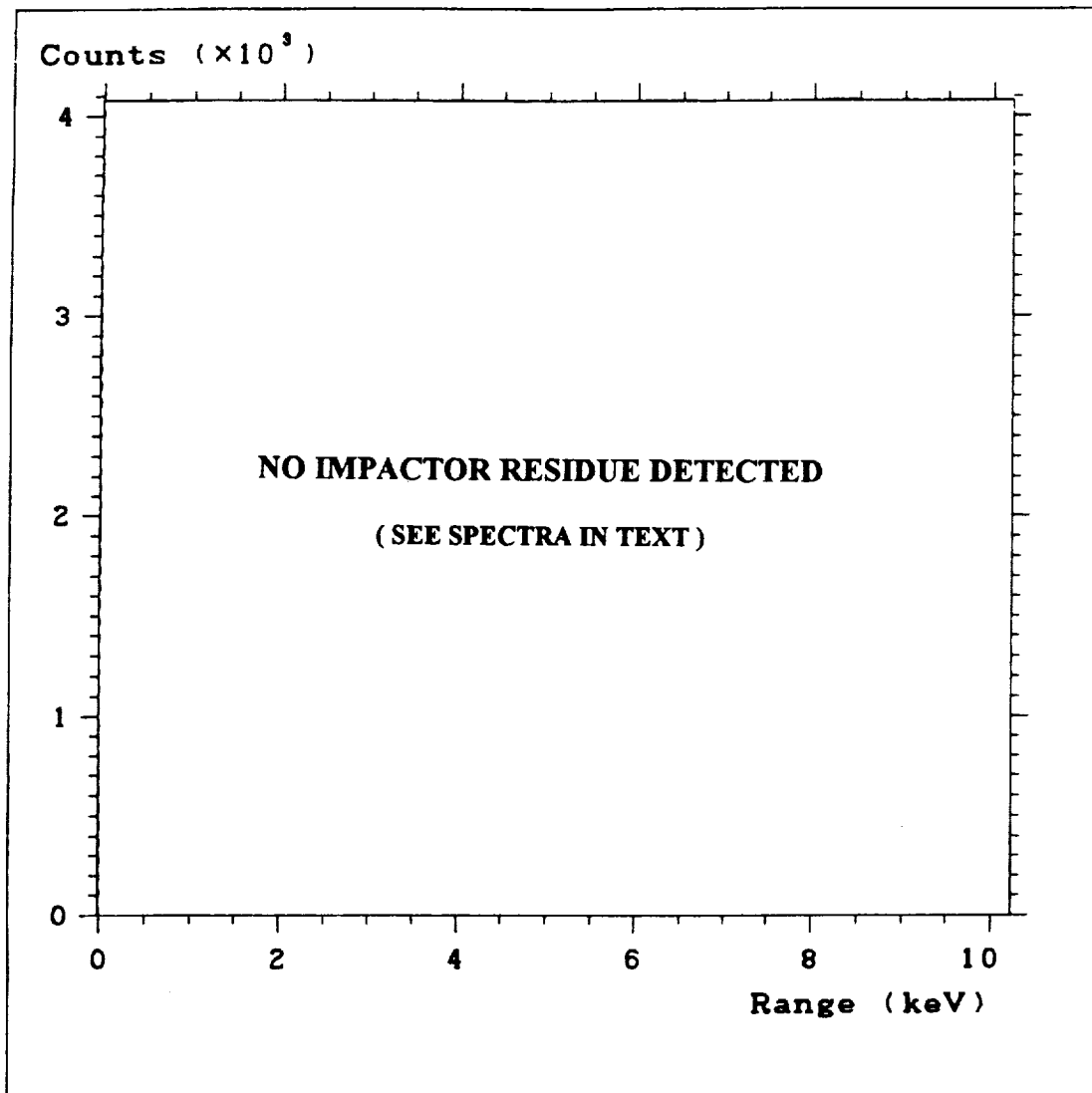


CLAMP NUMBER A04 C08

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	160	Unkown
002	400	Unkown

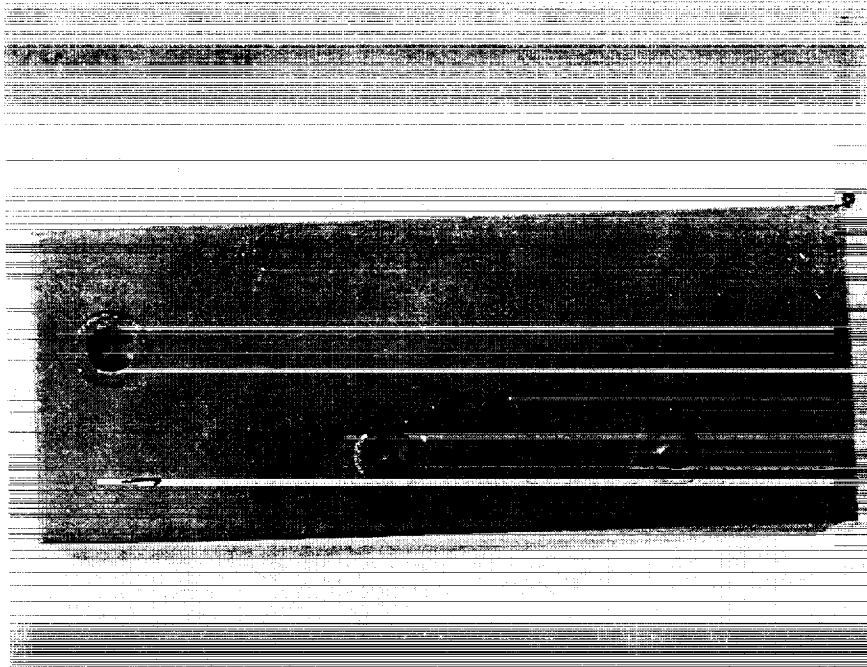


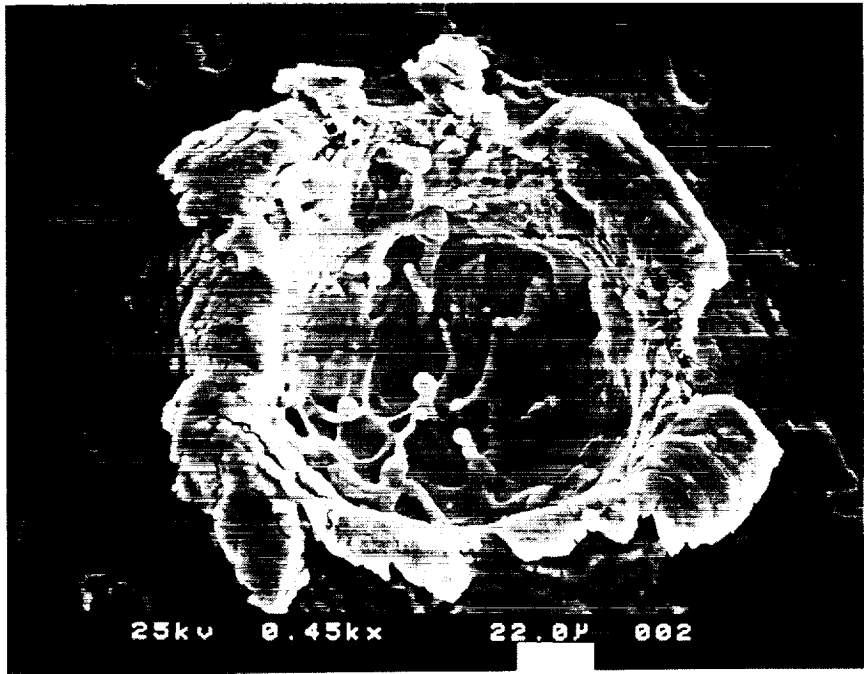
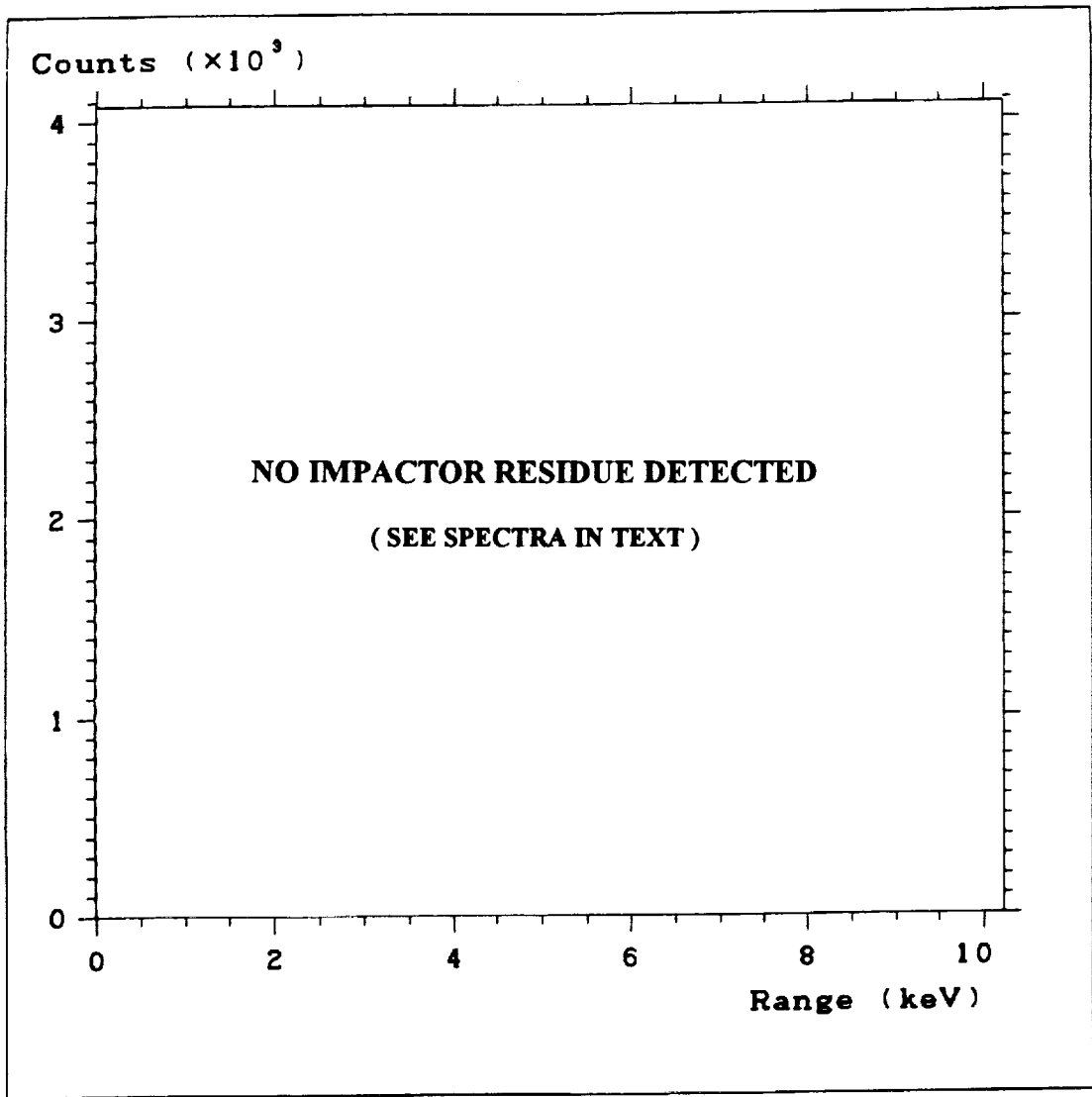




CLAMP NUMBER A05 C03

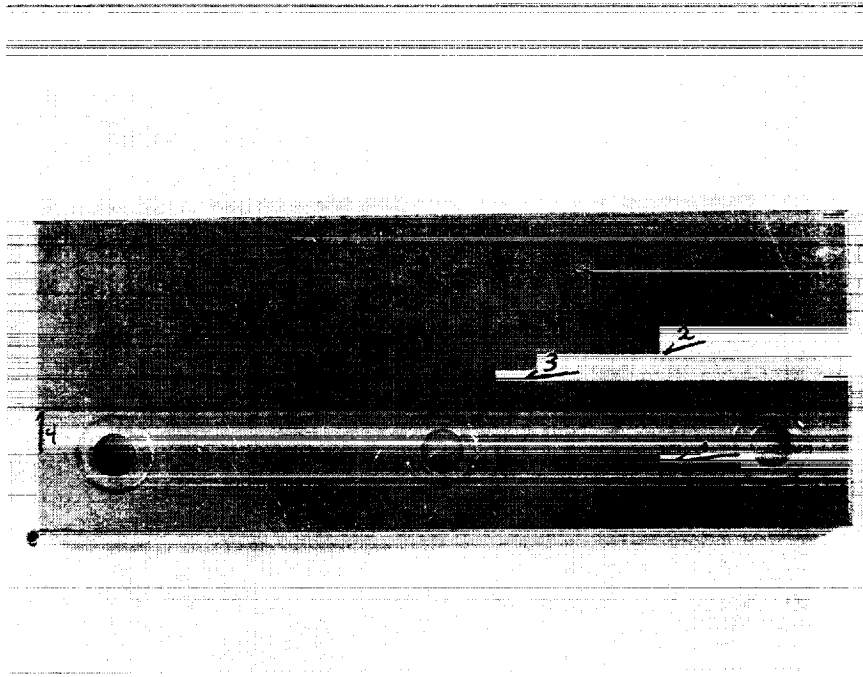
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	180	Unkown

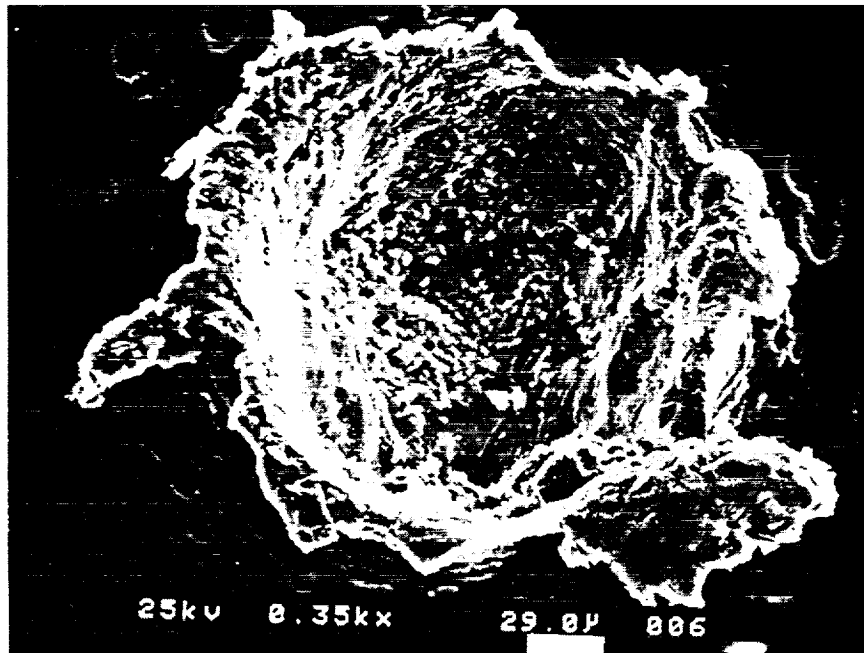
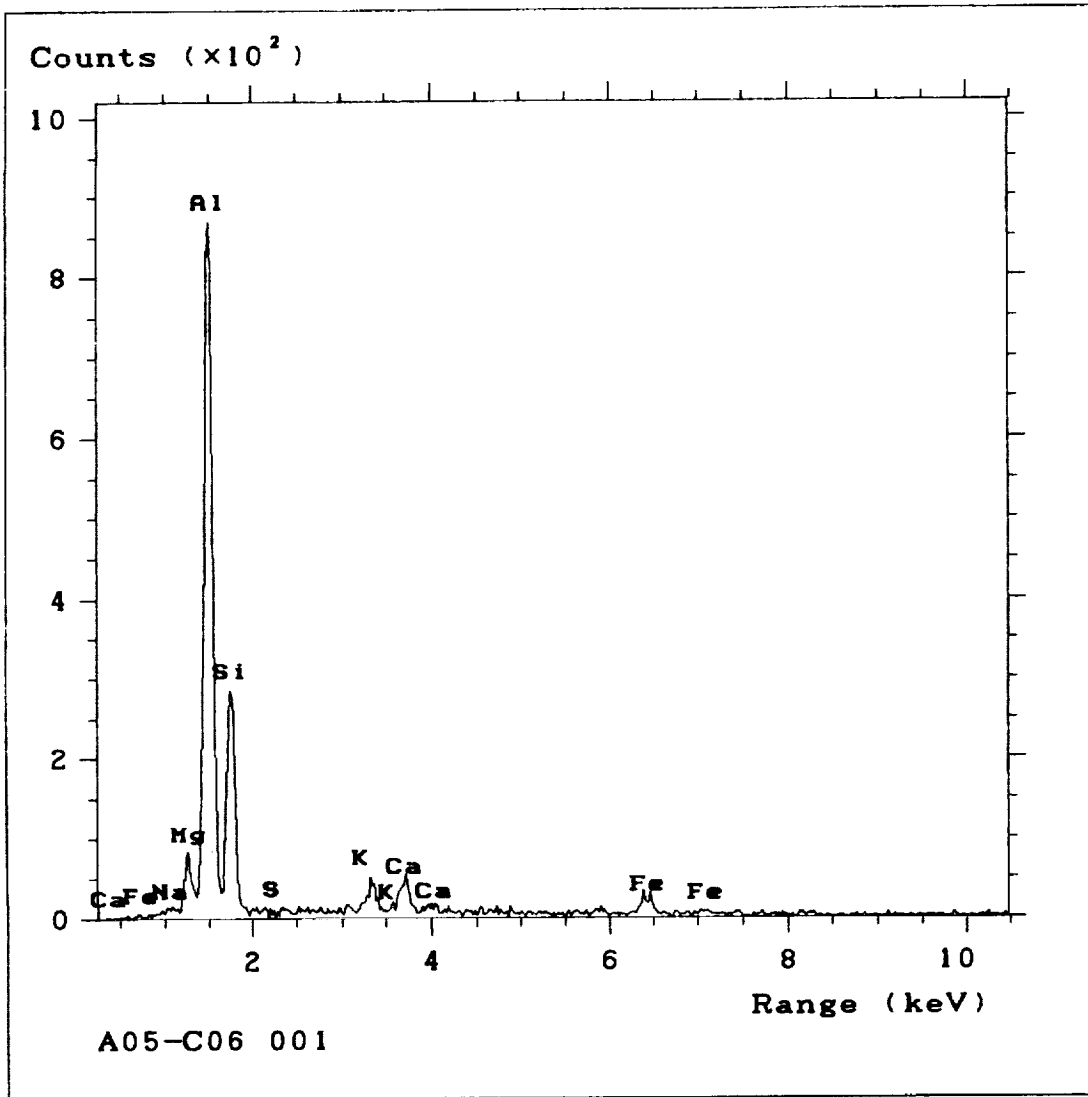


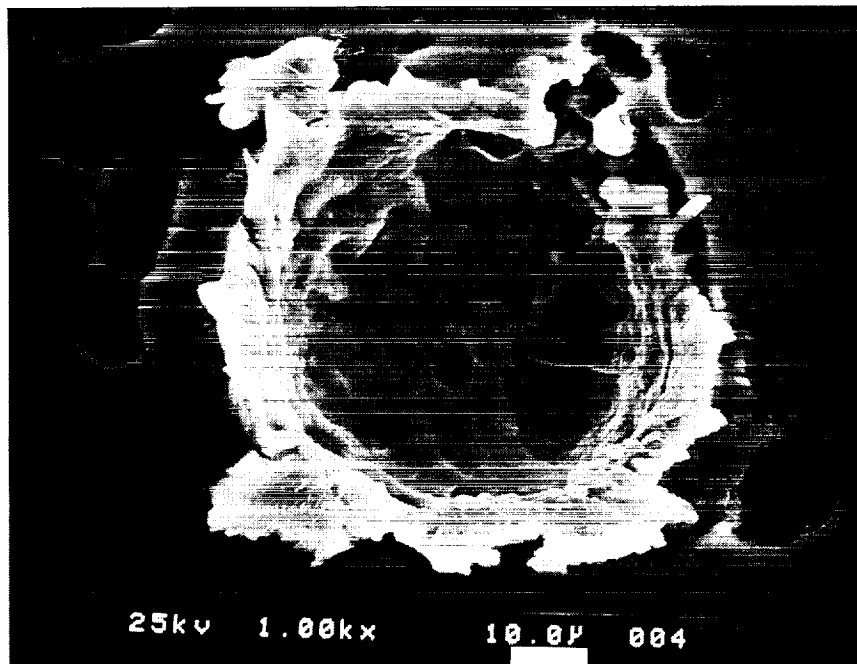
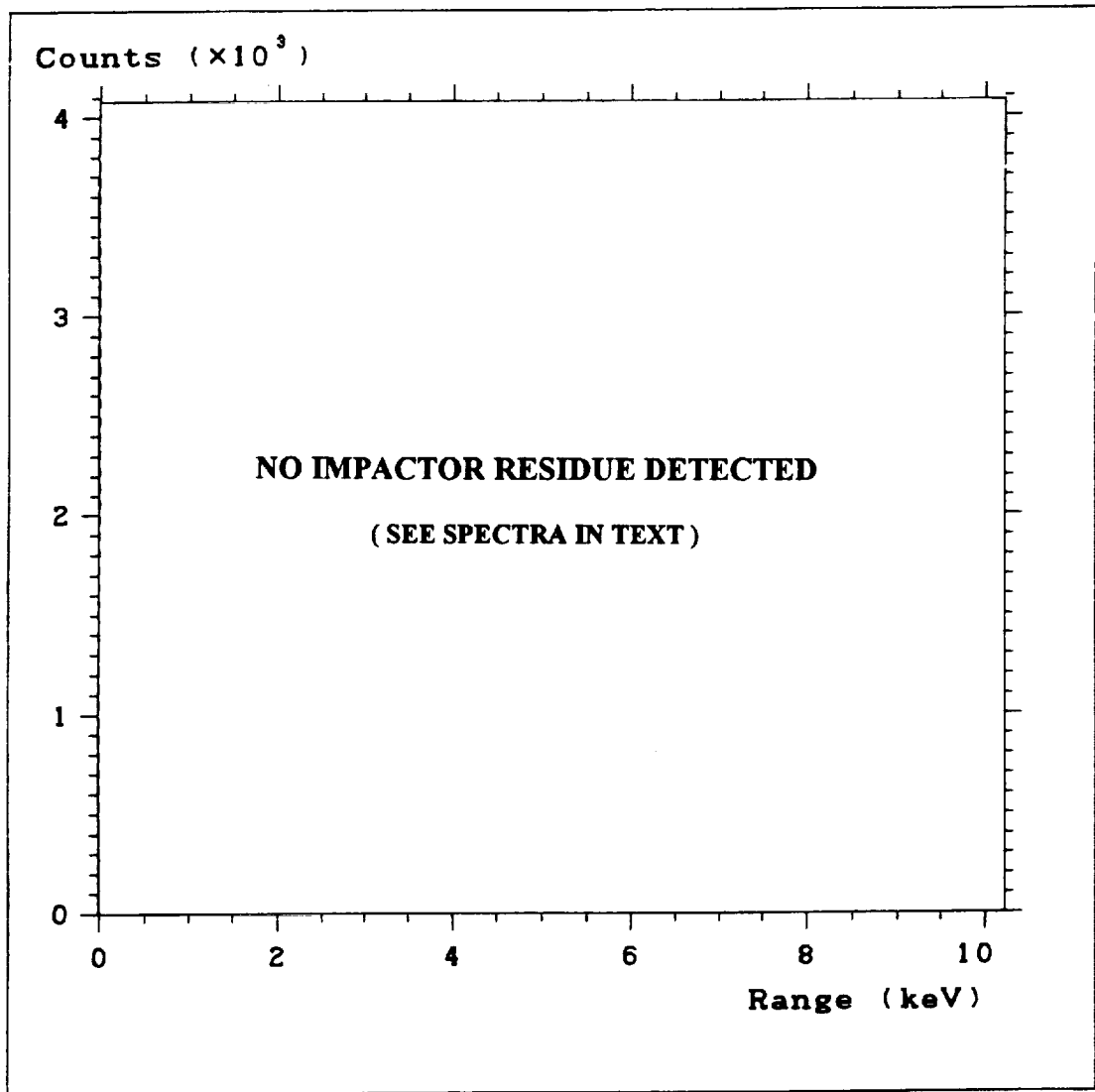


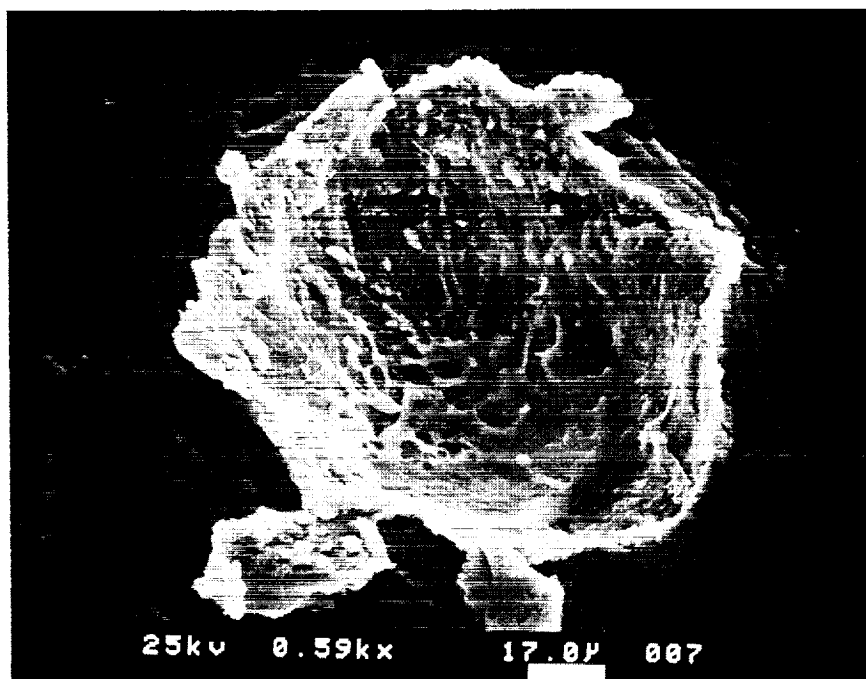
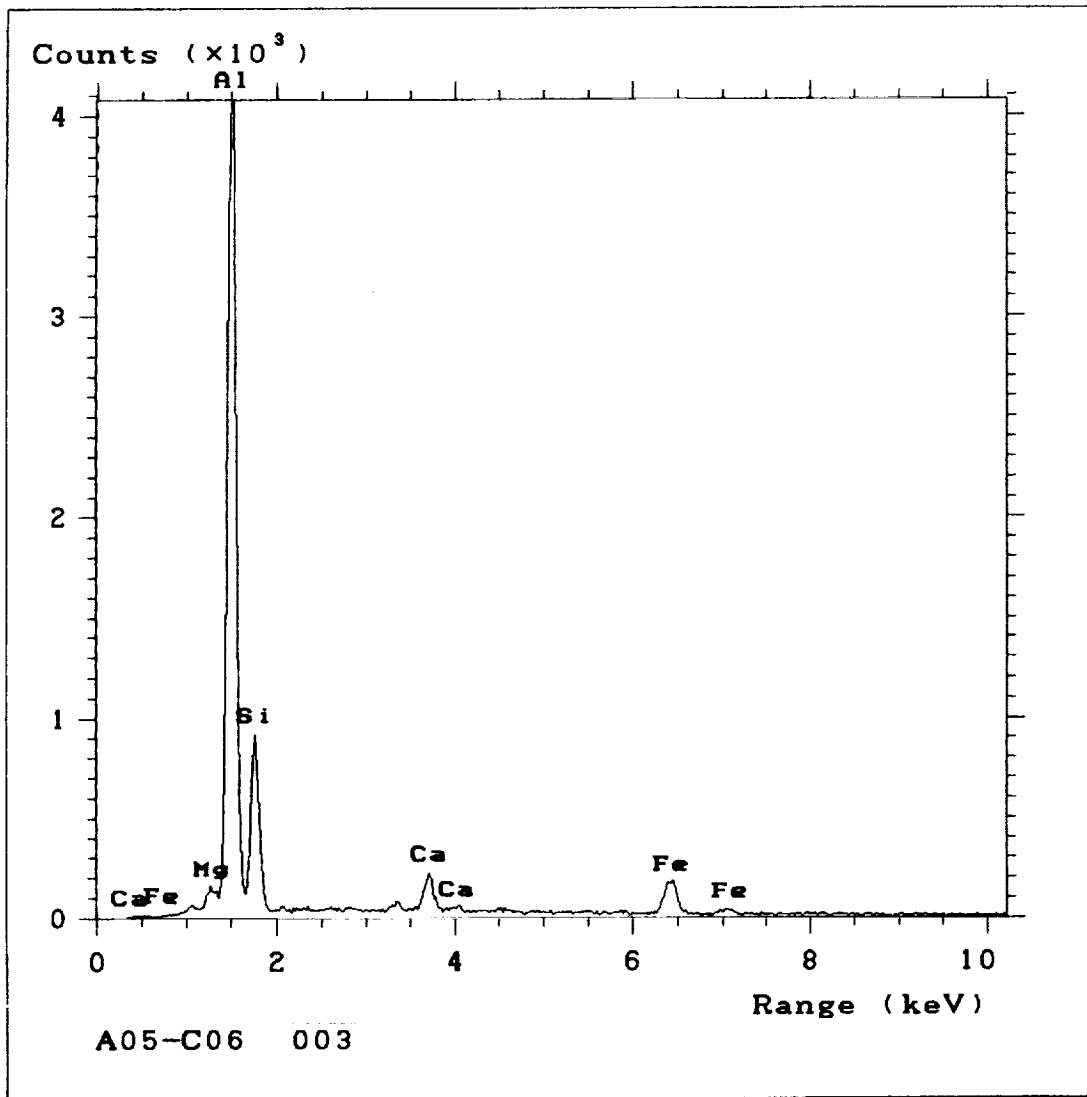
CLAMP NUMBER A05 C06

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	250	Si, Ca, S, K, Fe
002	70	Unkown
003	140	Trace
004	50	Unkown
005	90	Unkown



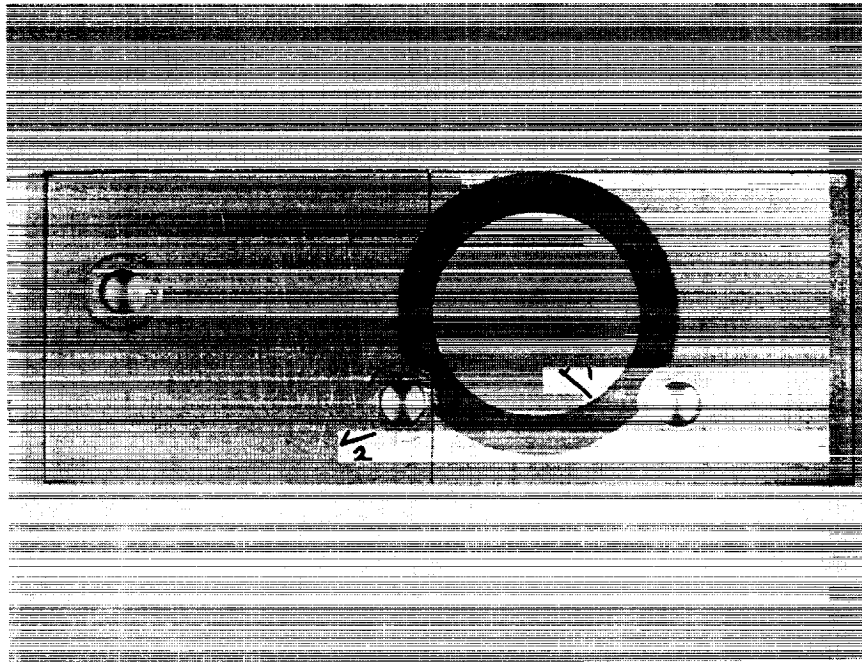


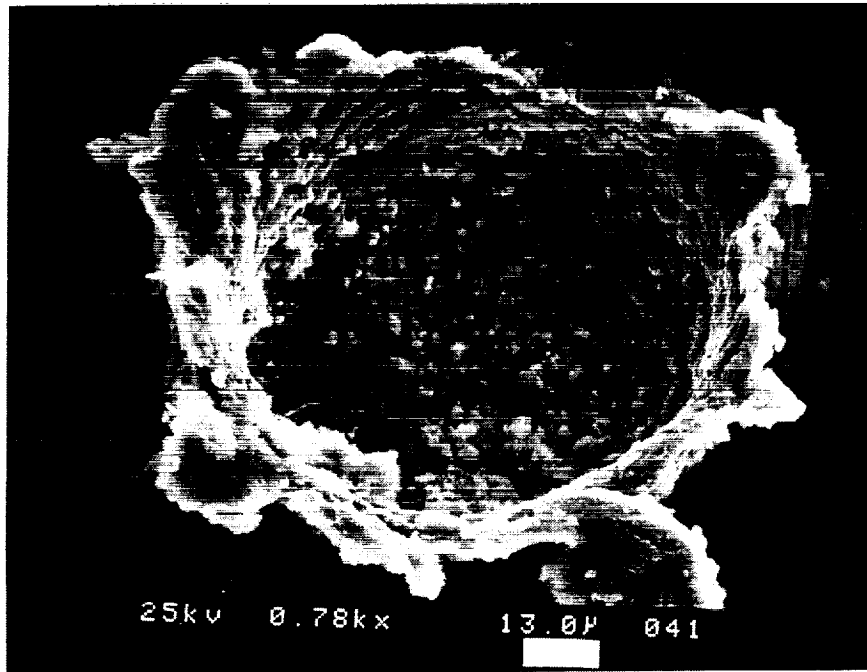
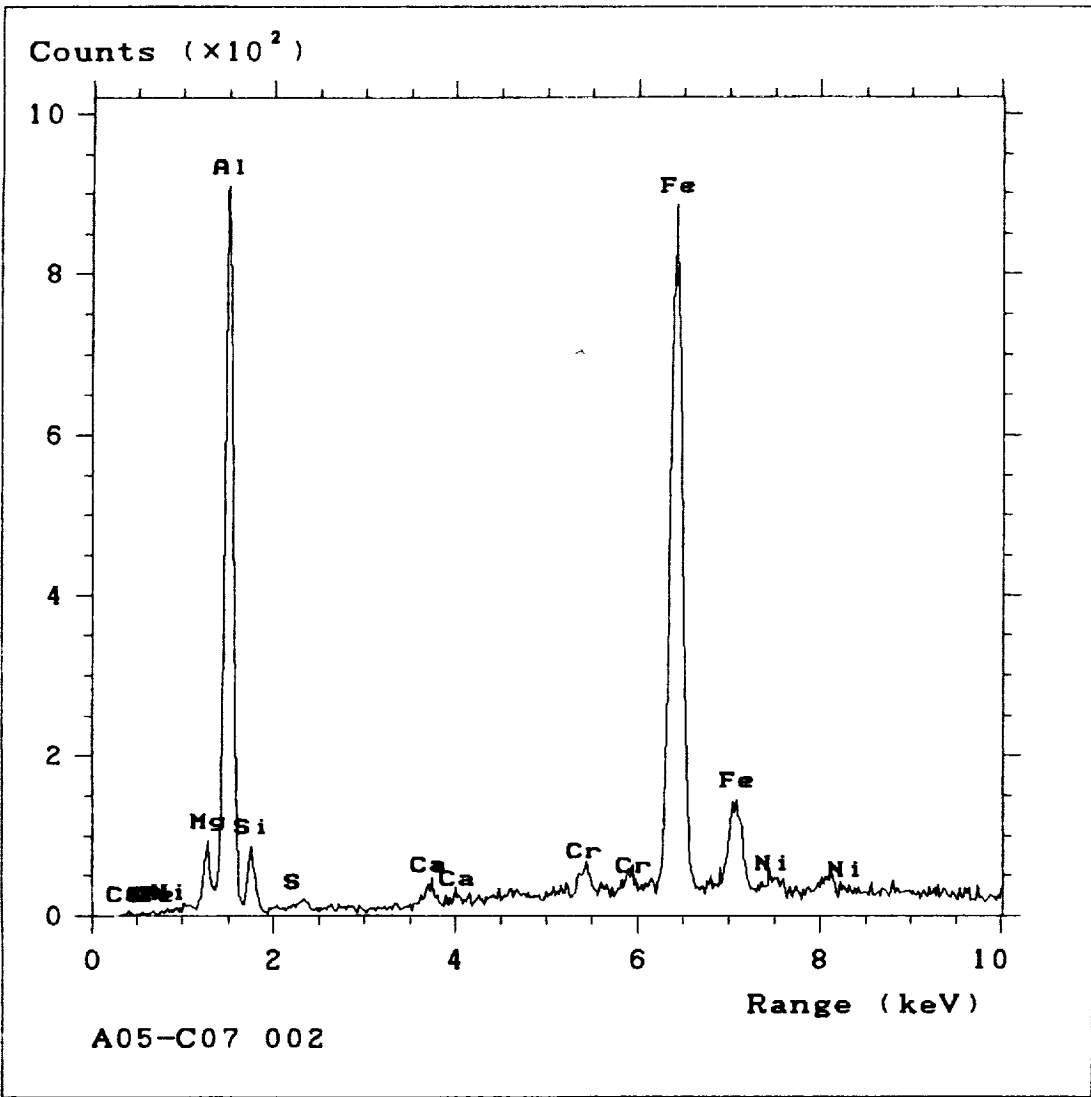




CLAMP NUMBER A05 C07

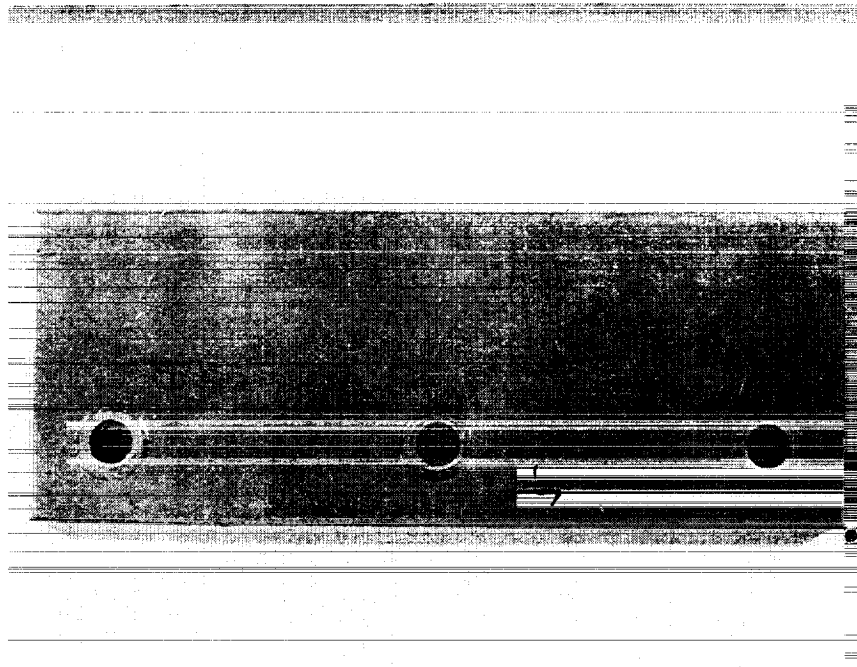
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	400	Paint Patch
002	100	Mg, Si, Ca, Fe, S

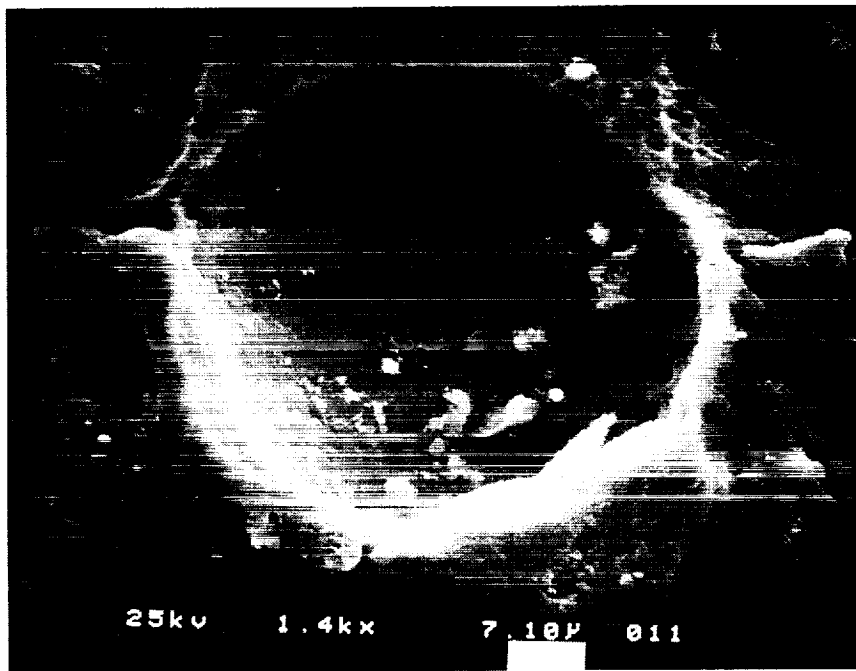
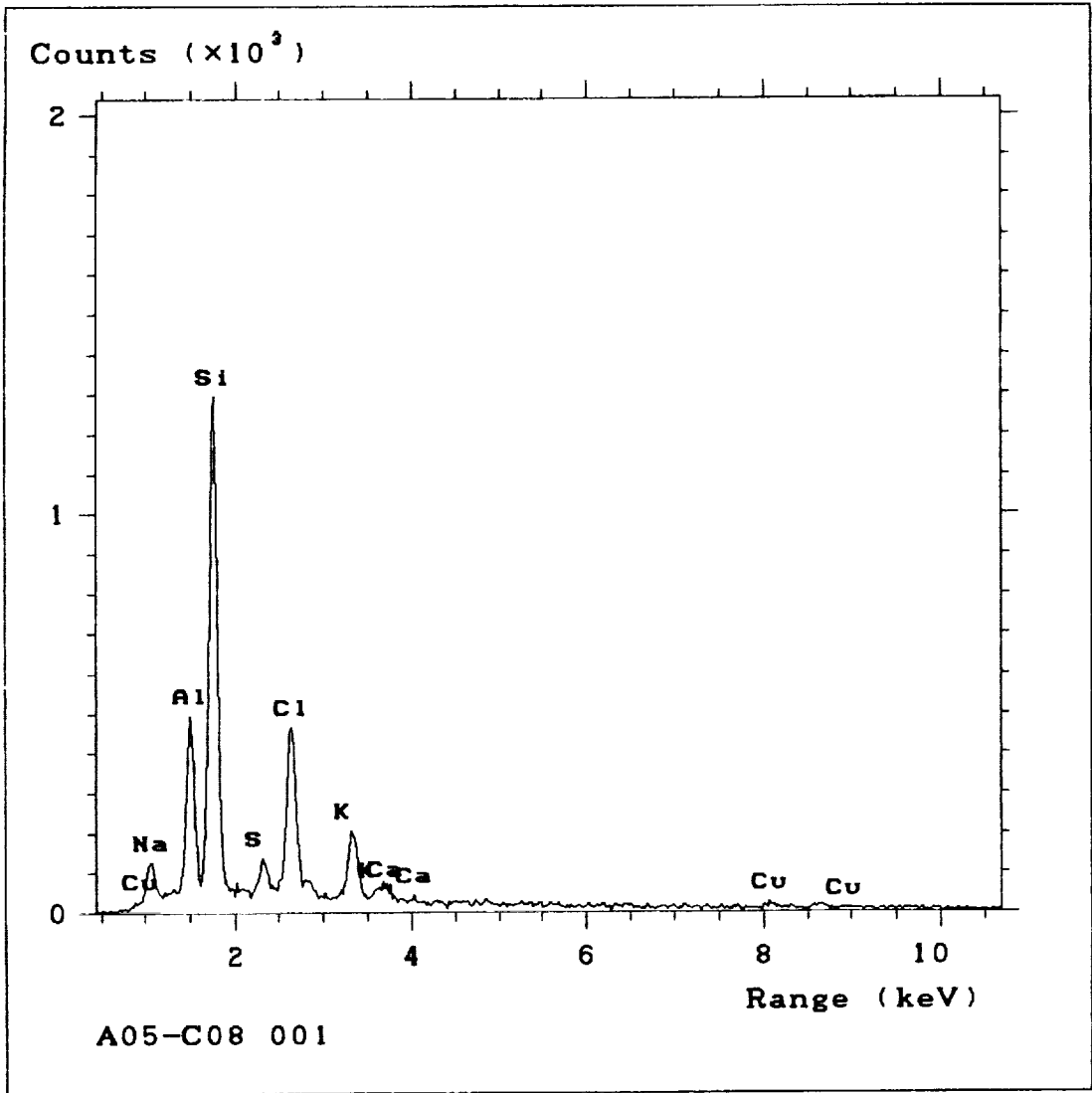




CLAMP NUMBER A05 CO8

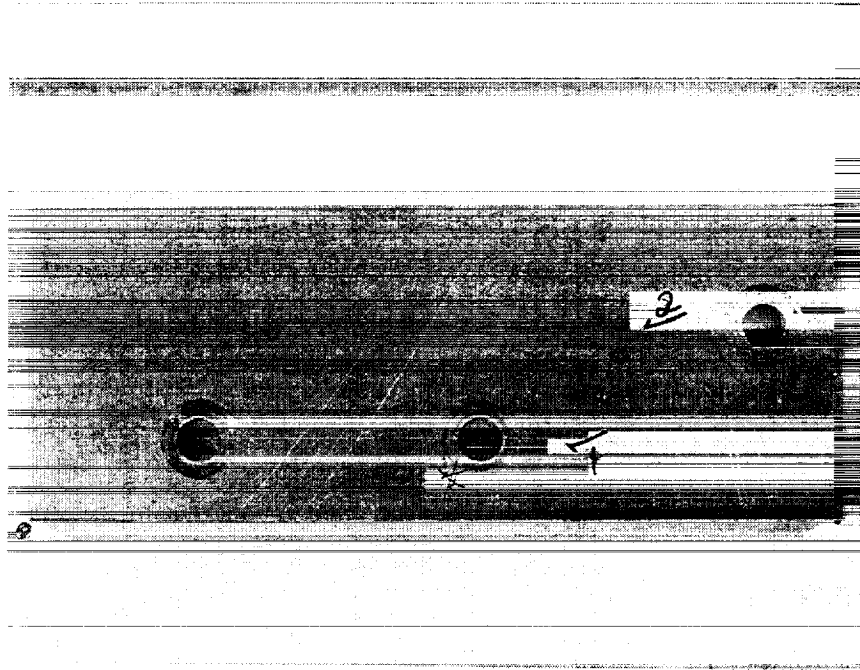
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	180	Contamination

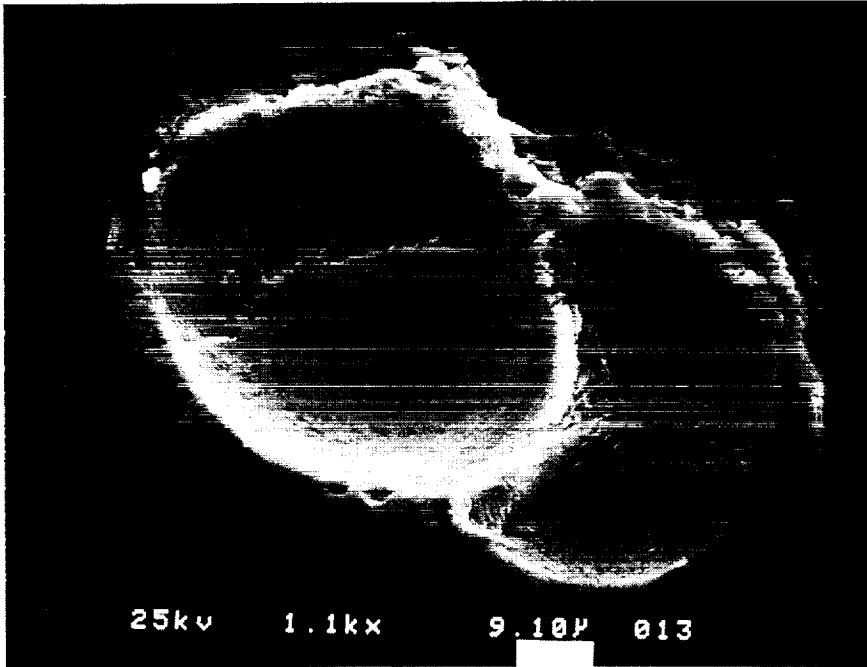
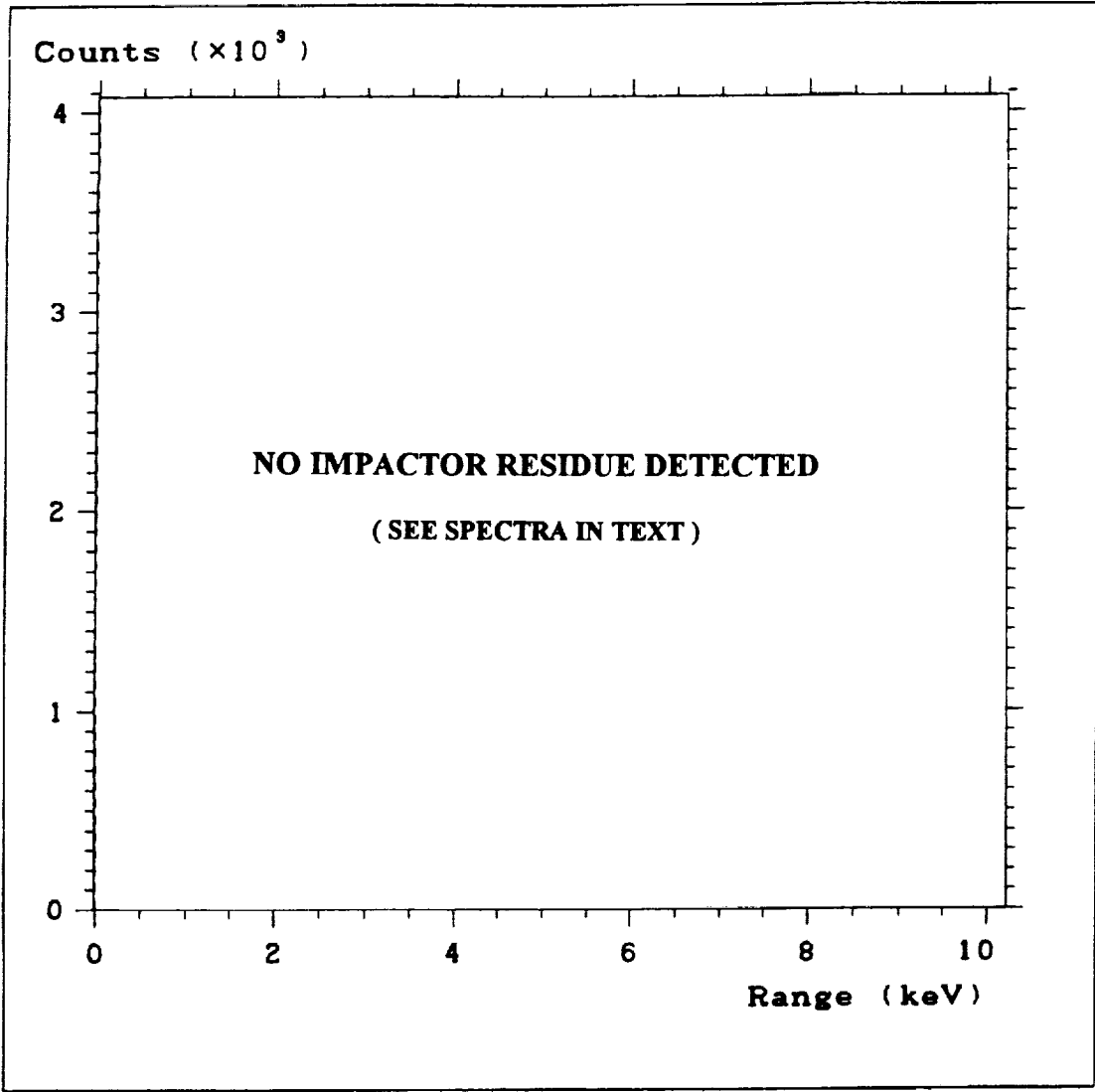


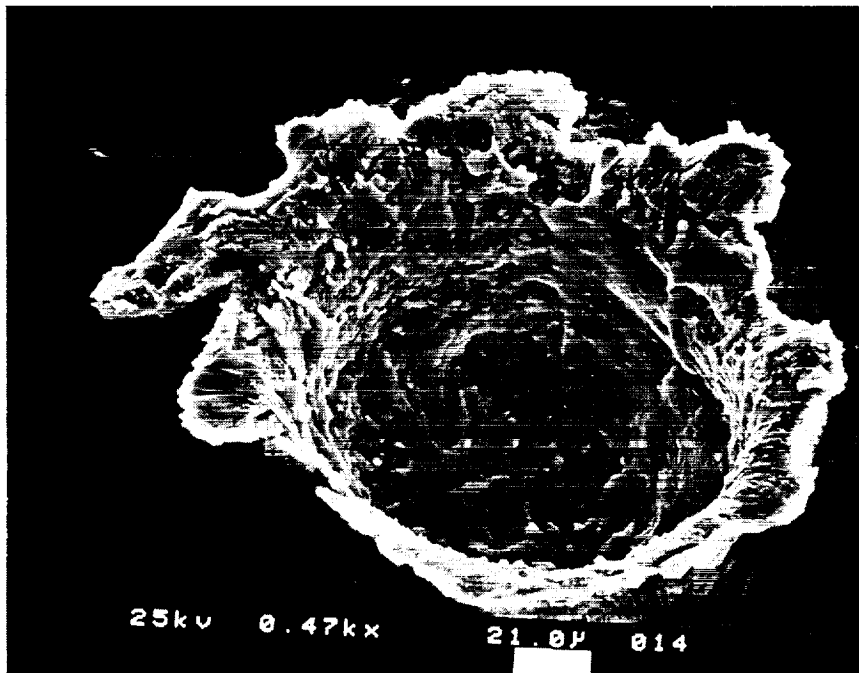
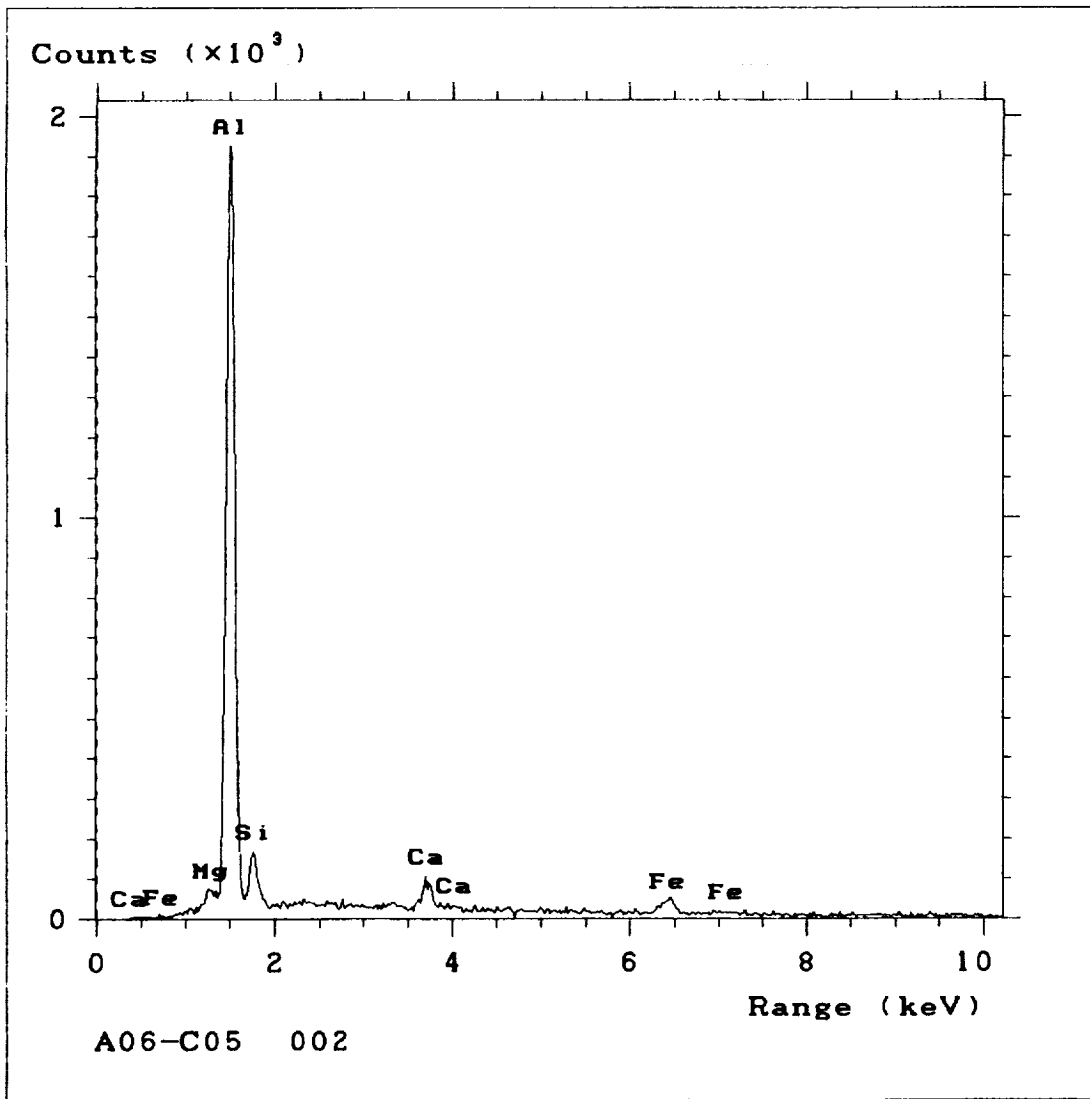


CLAMP NUMBER A06 C05

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	70	Clamp Flaw
002	200	Trace

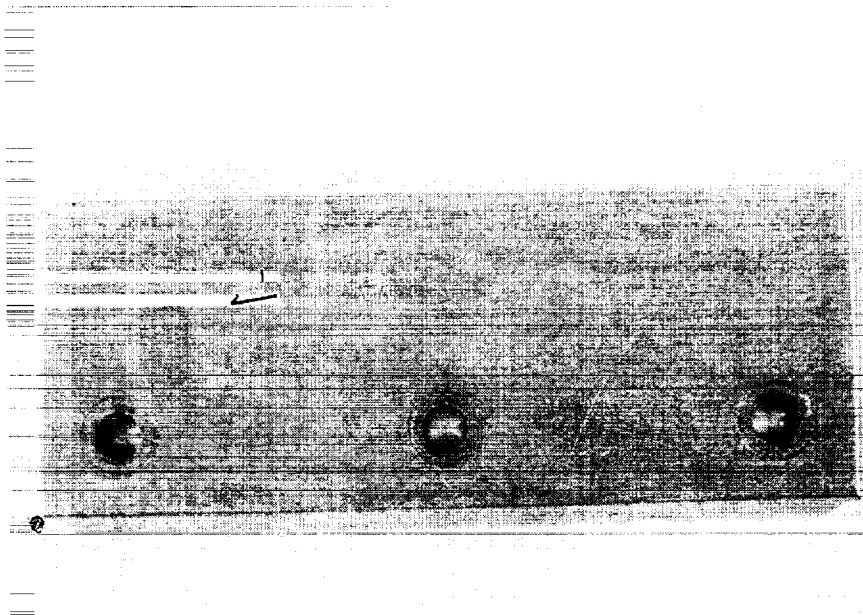


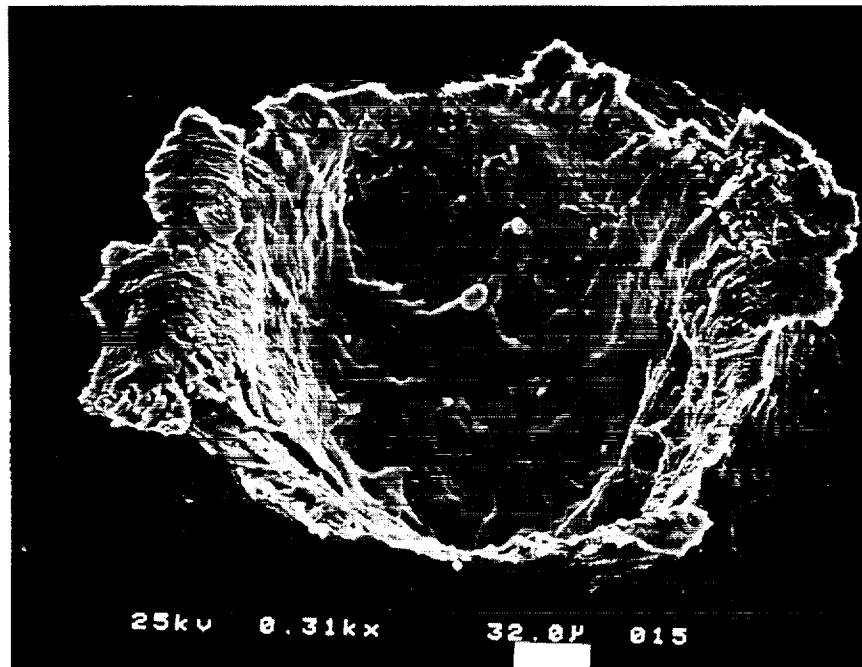
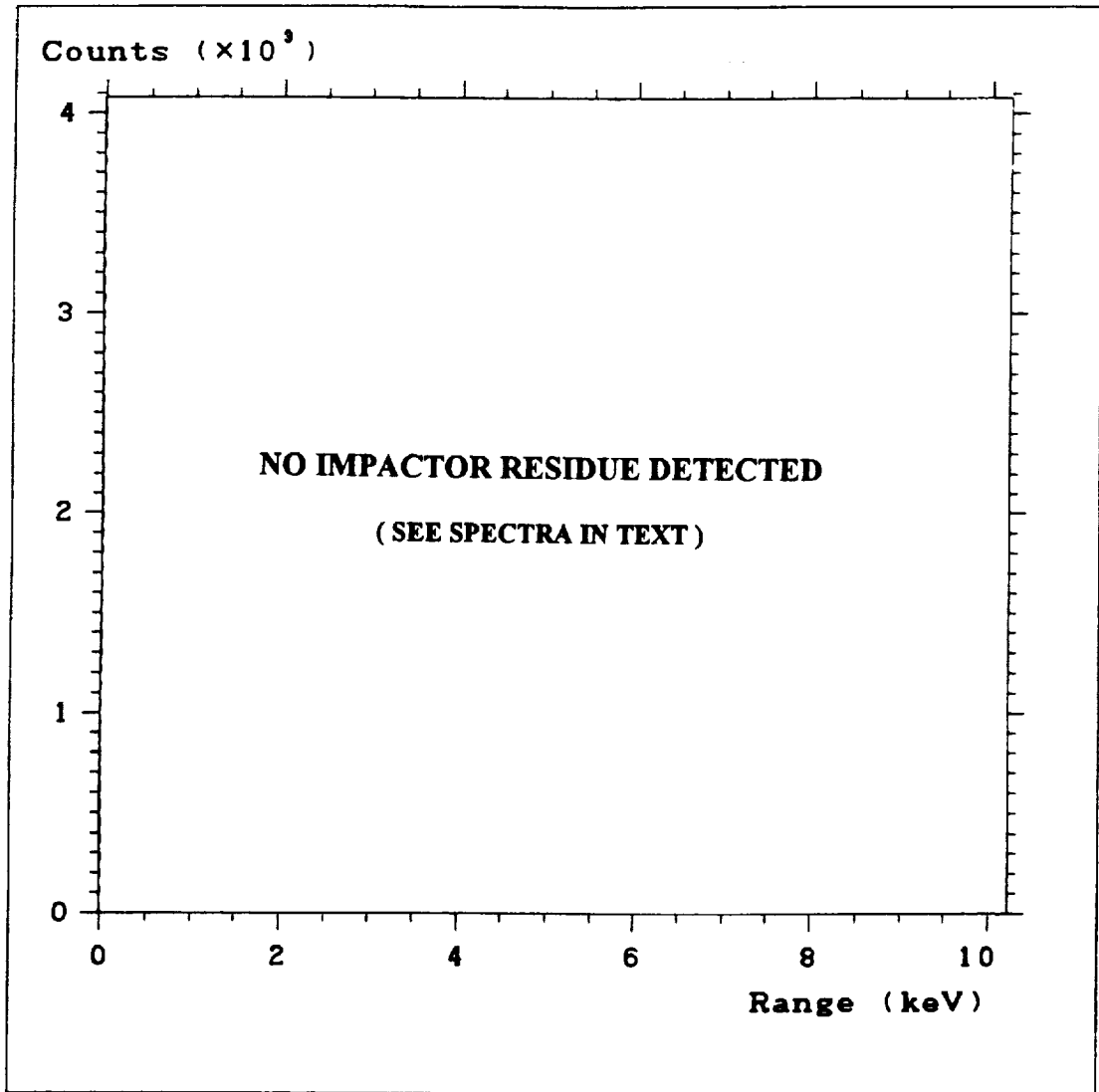




CLAMP NUMBER A06 C06

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	320	Unkown

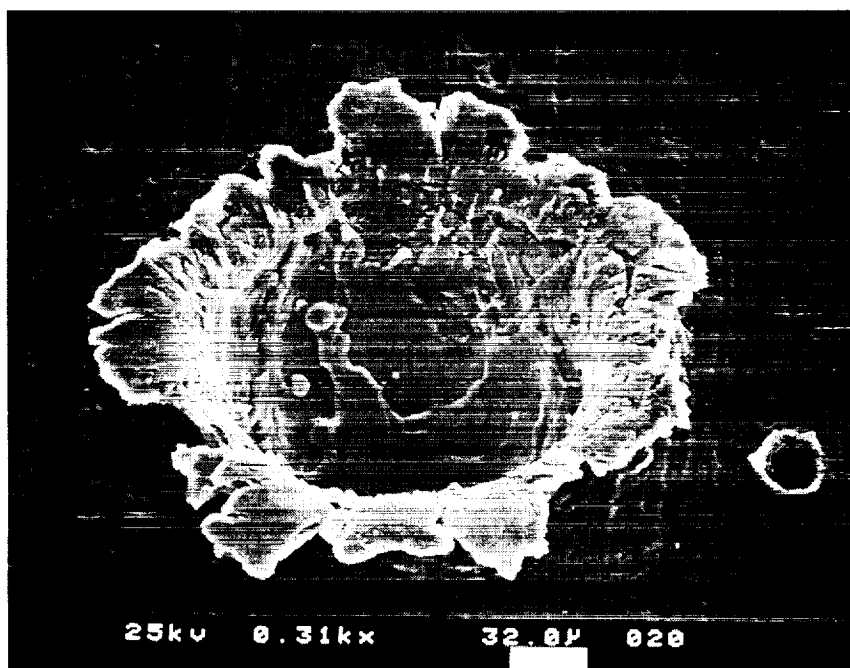
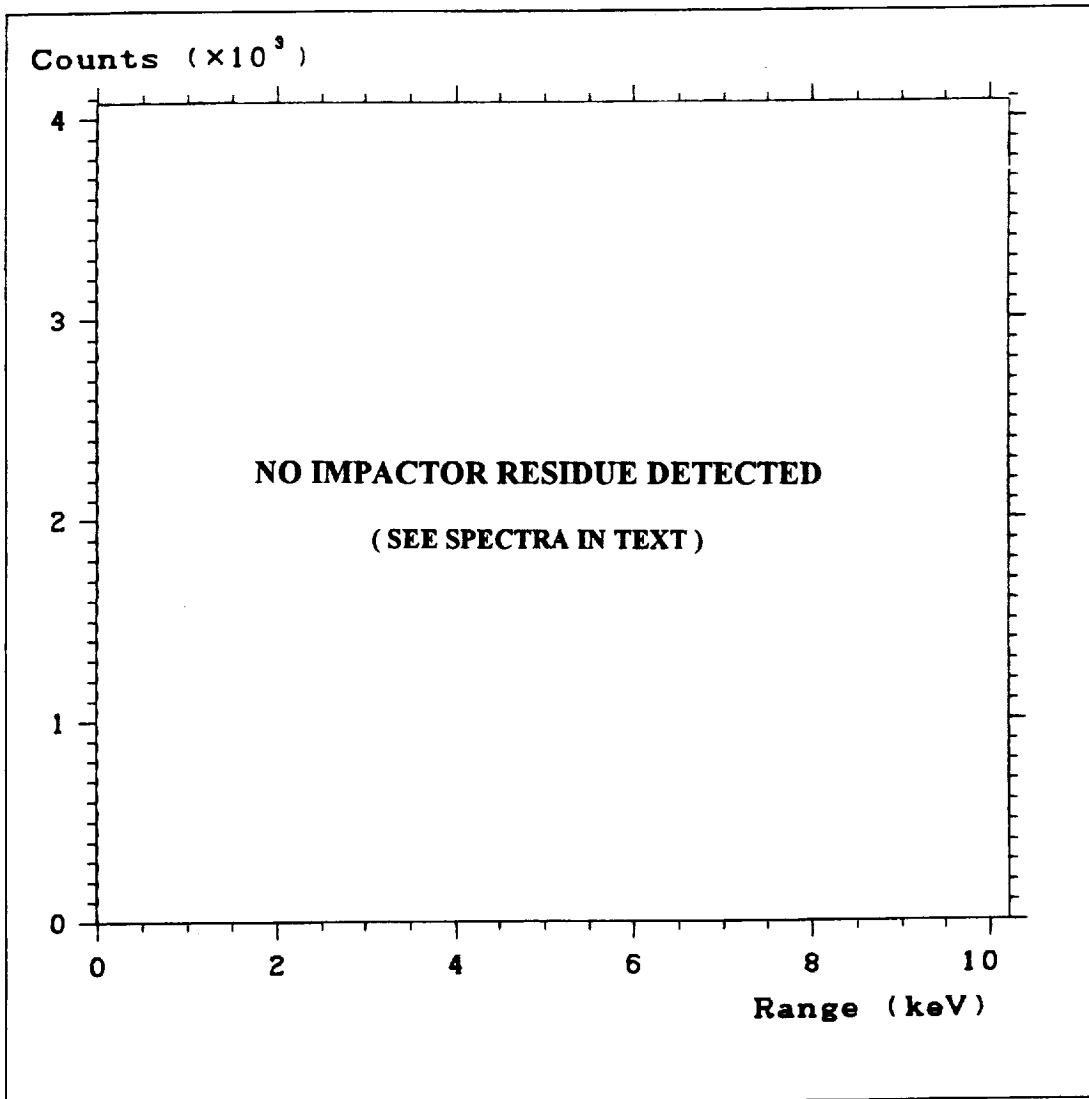


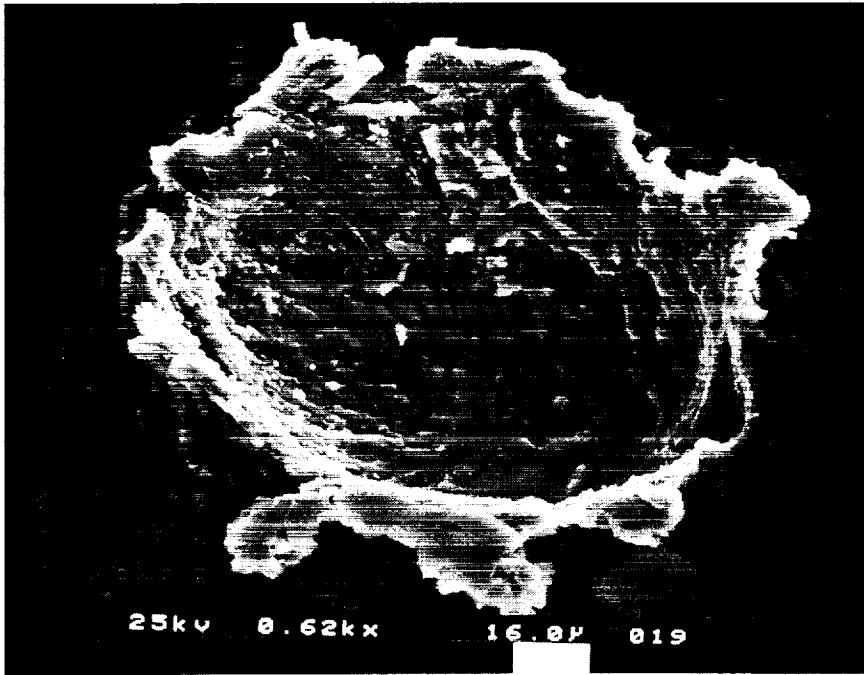
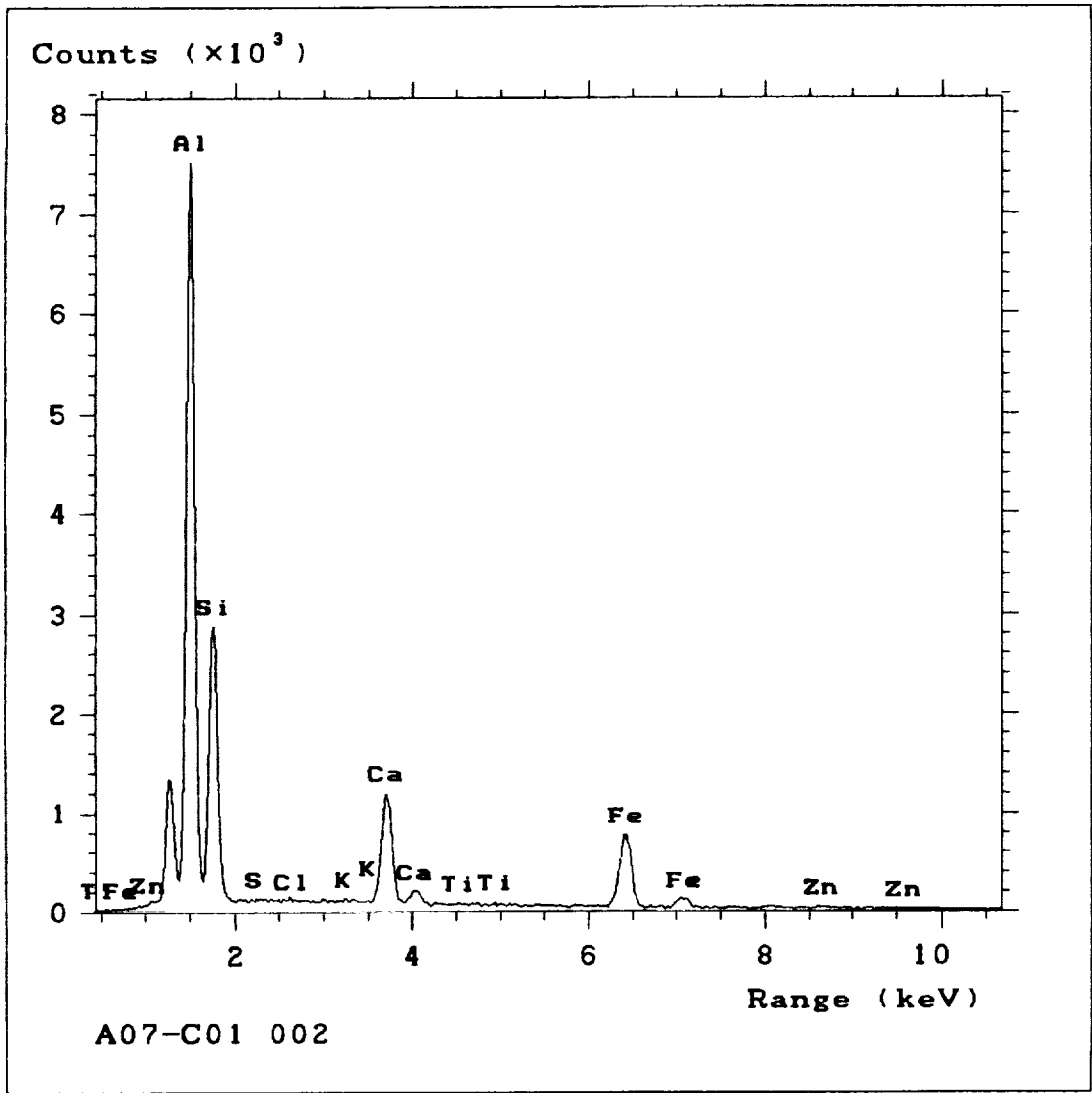


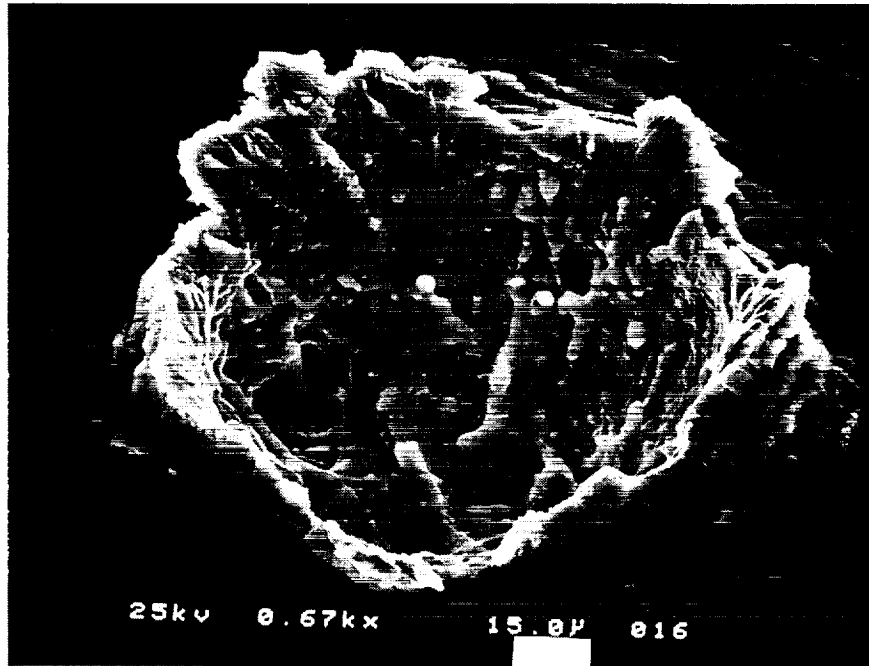
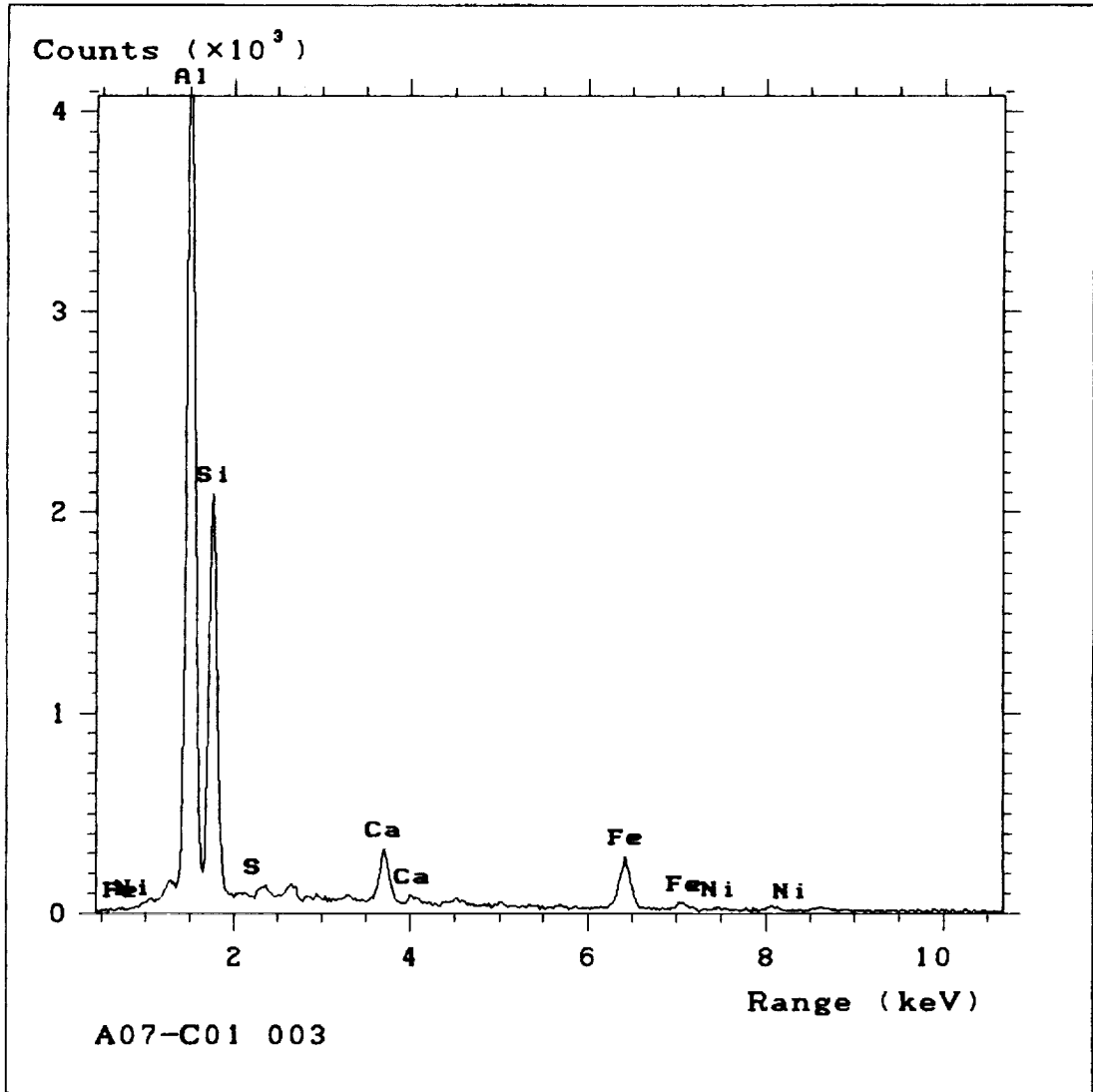
CLAMP NUMBER A07 CO1

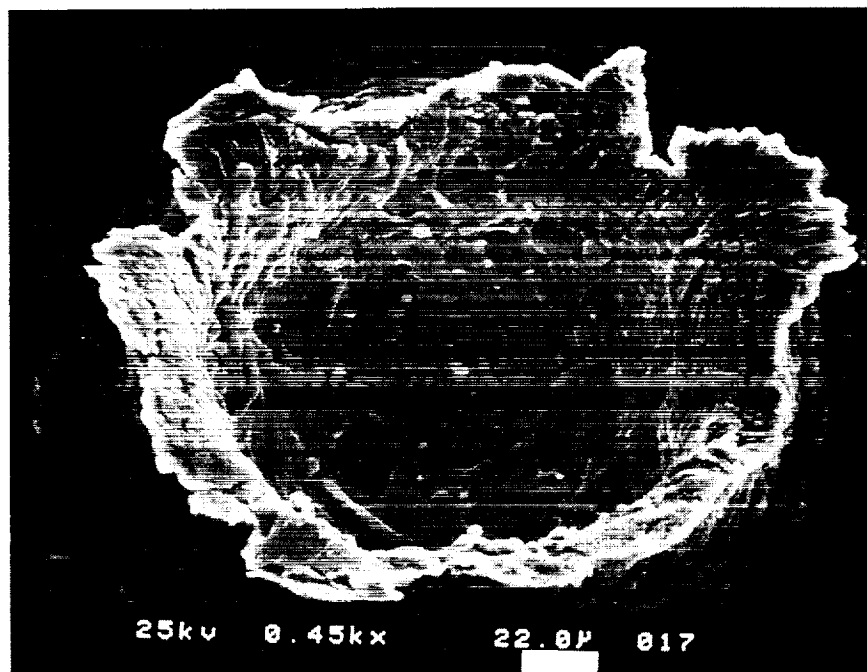
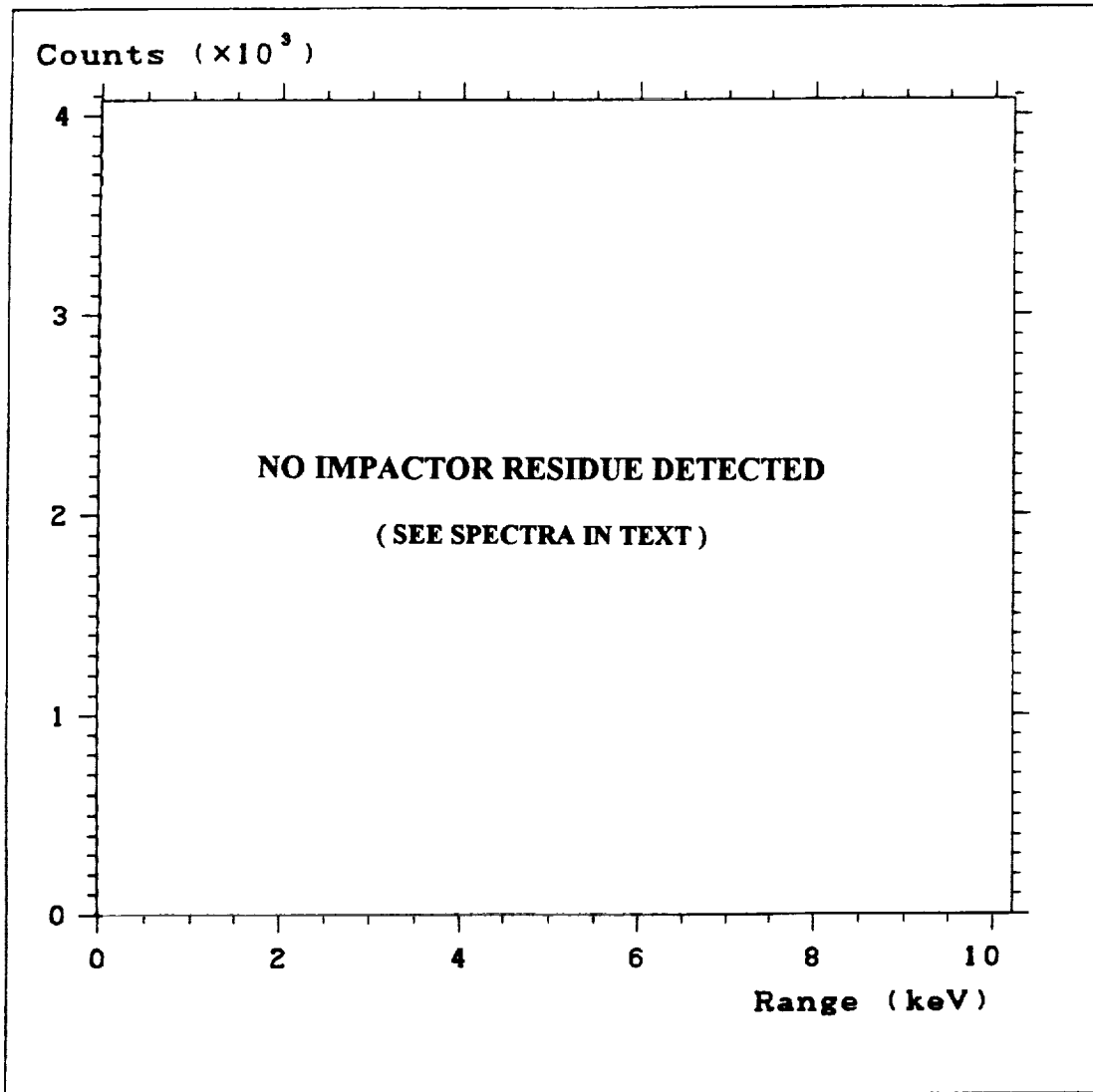
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	210	Unkown
002	120	Si, Ca, Fe
003	110	Si, Ca, S, Fe
004	210	Unkown
005	130	Trace

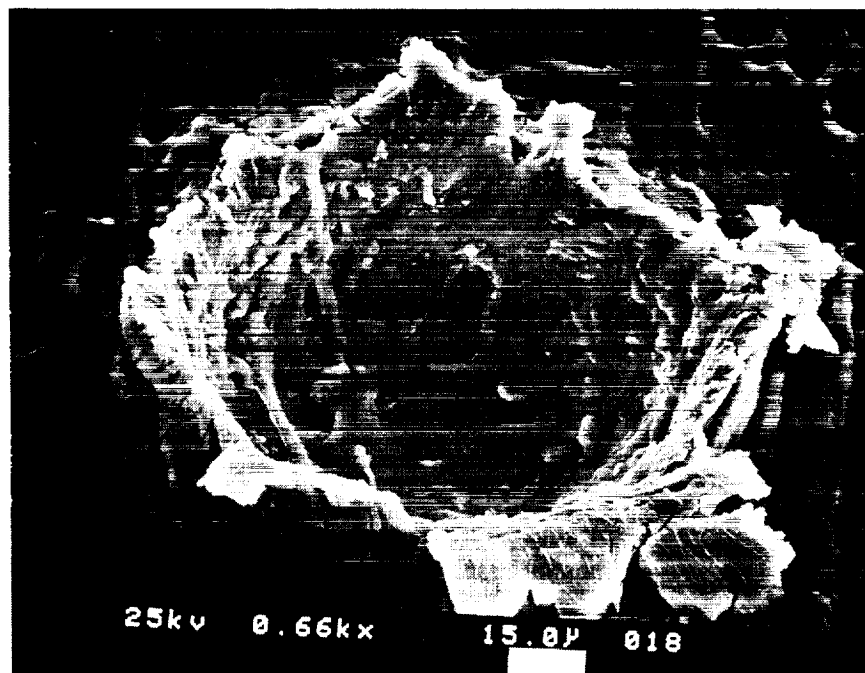
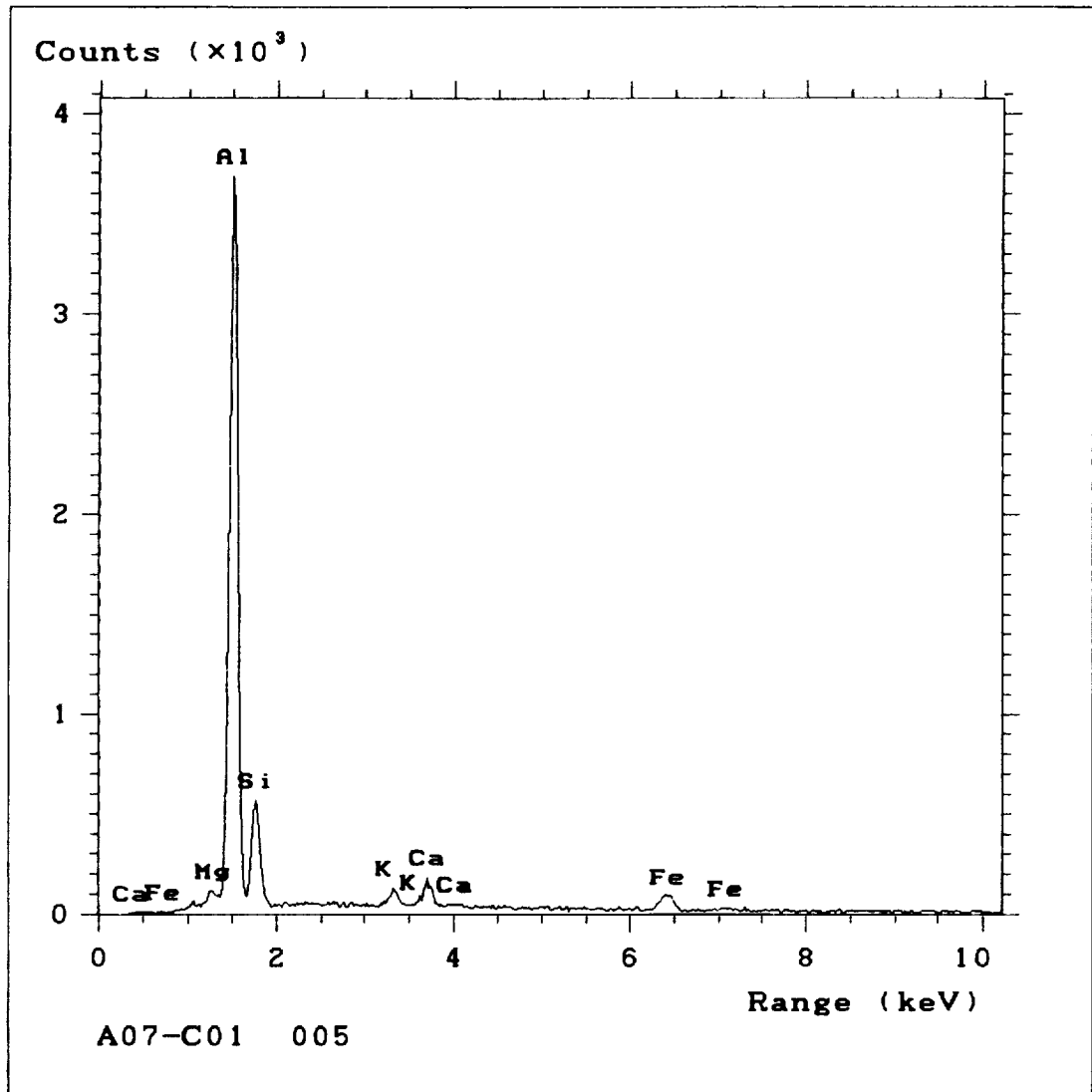






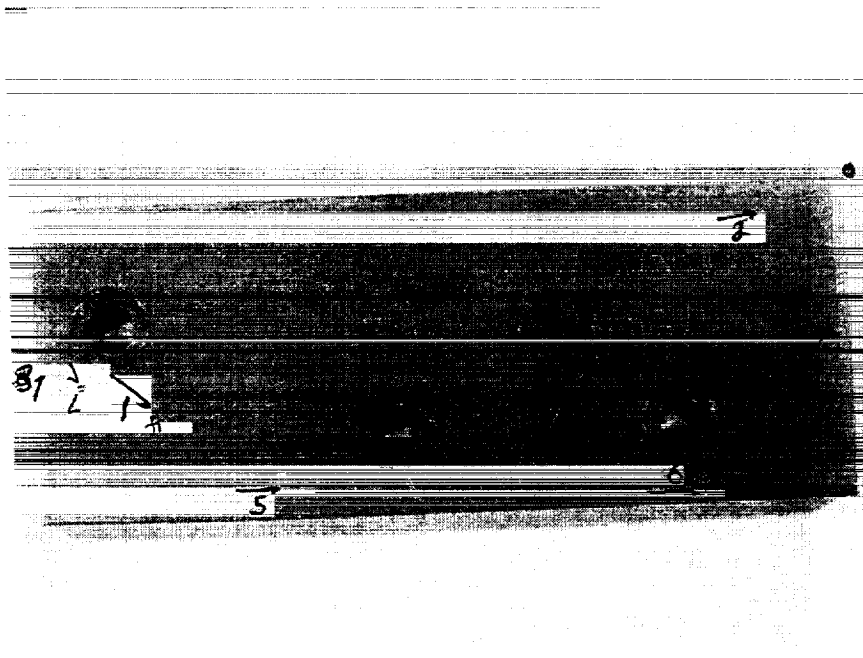


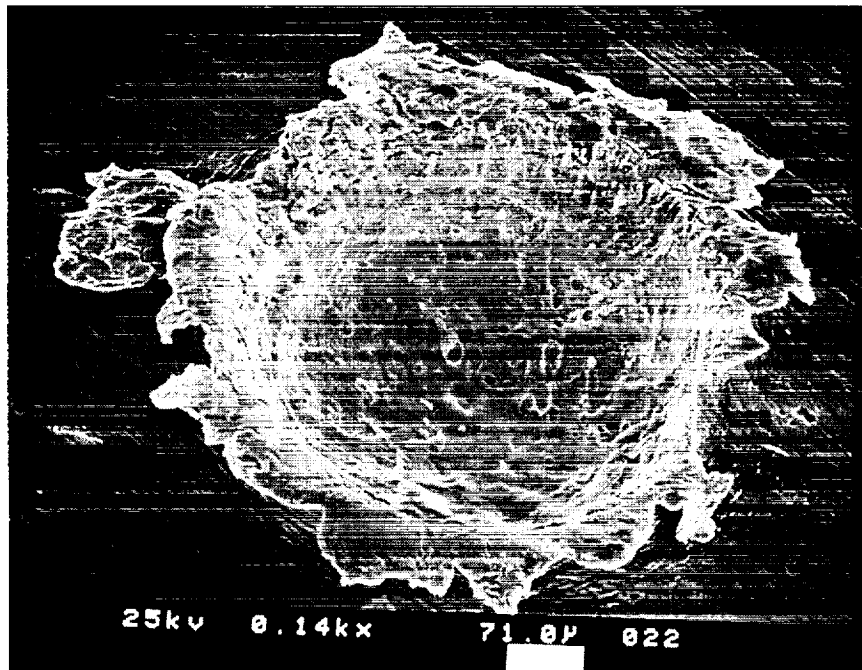
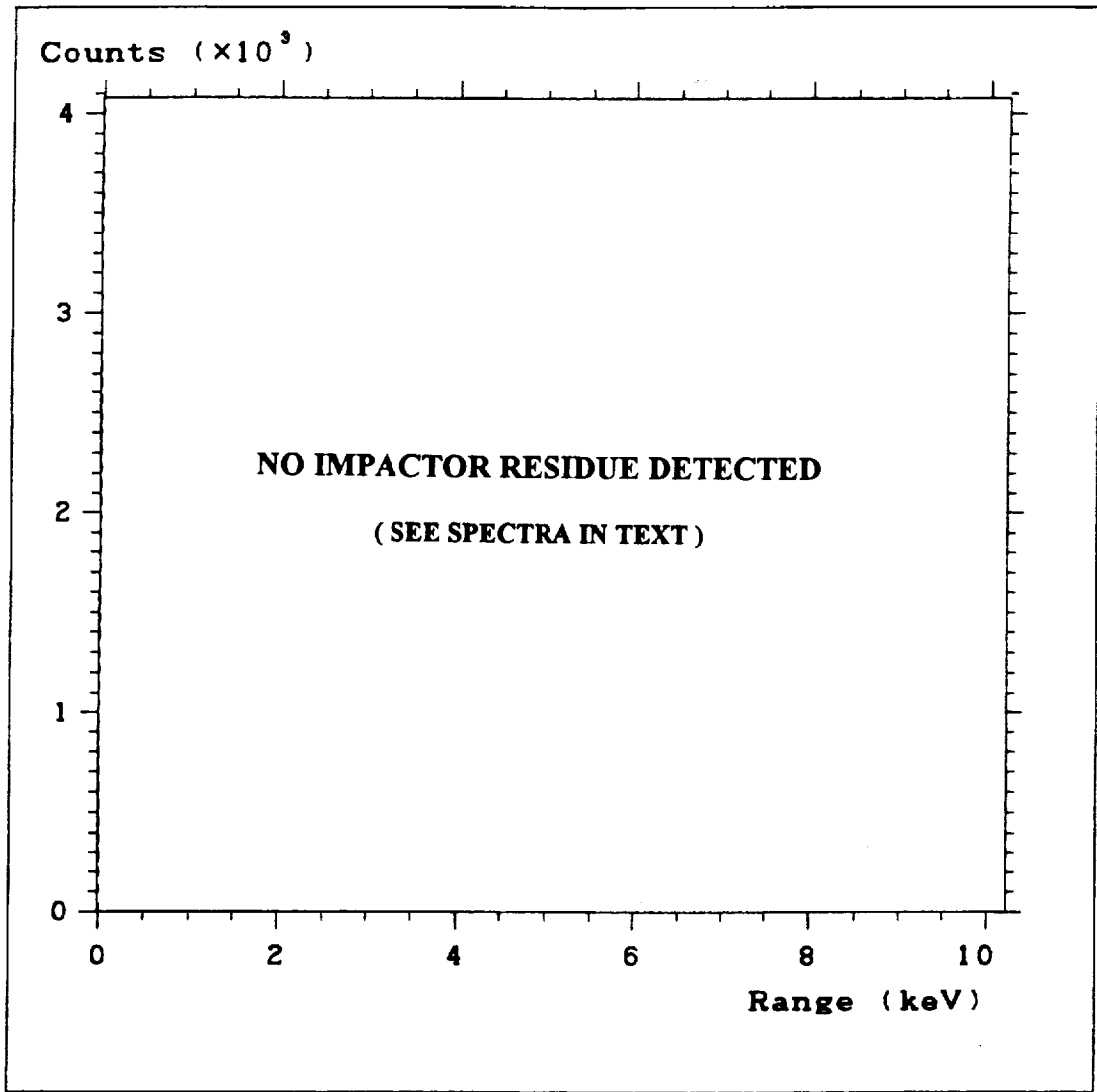


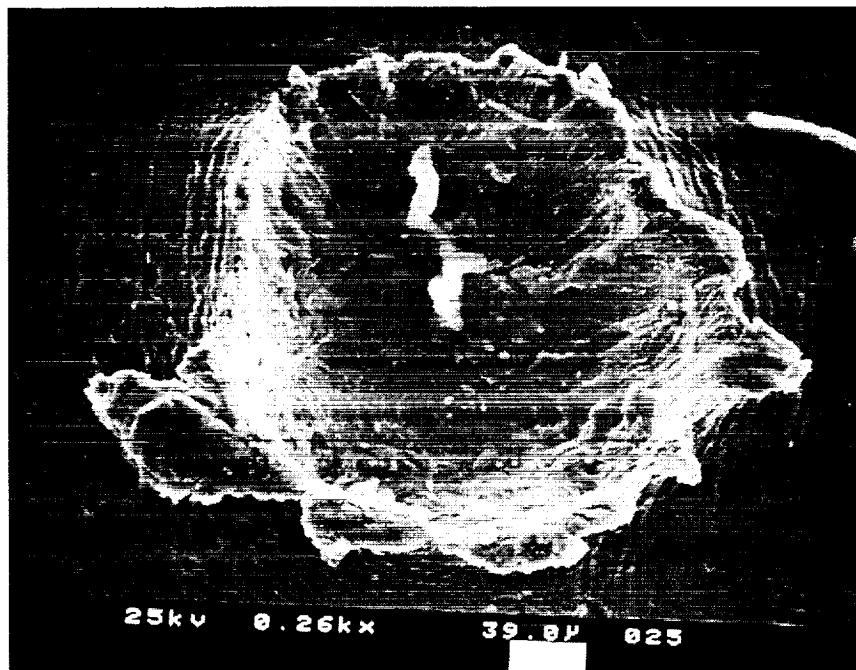
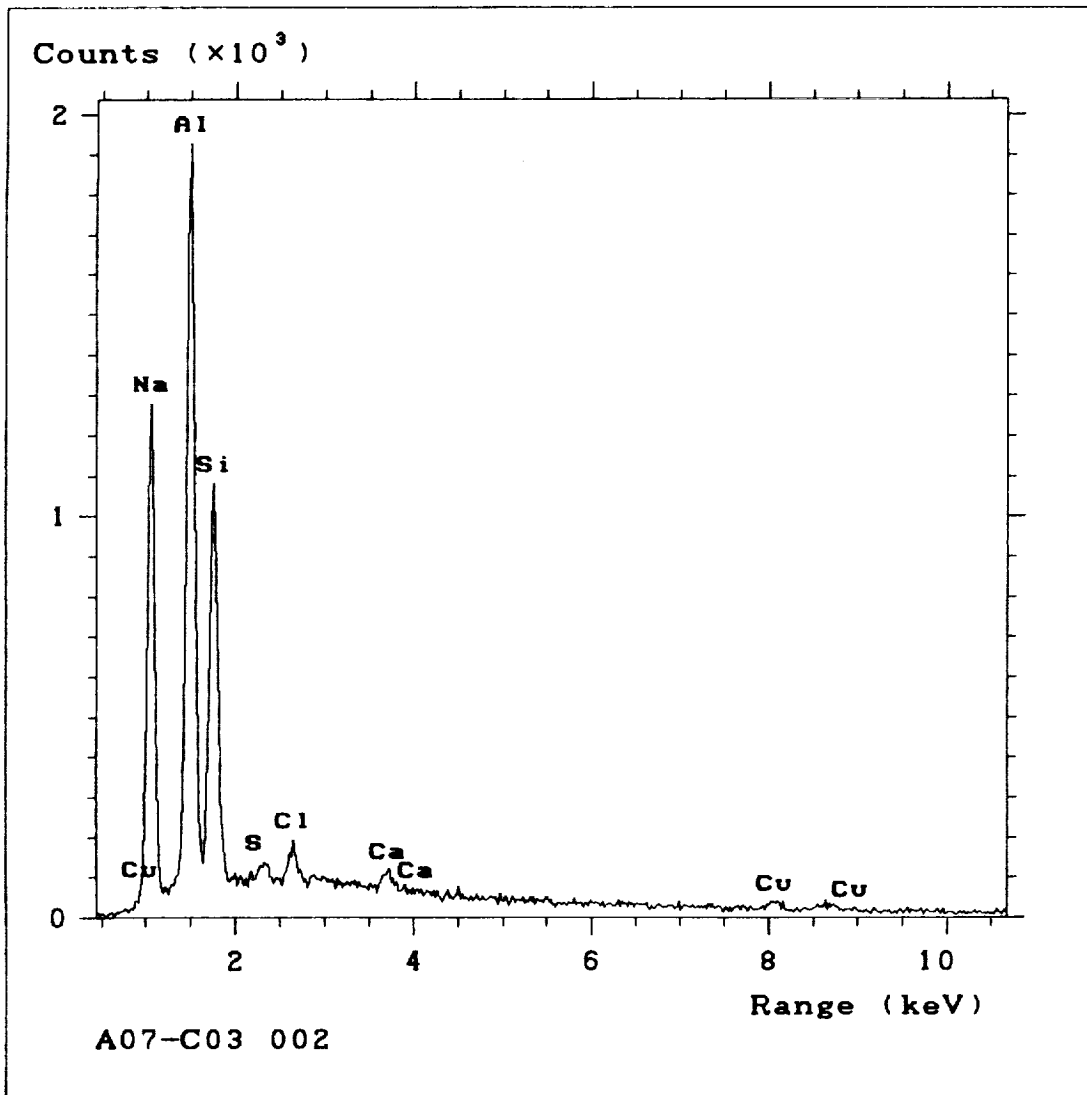


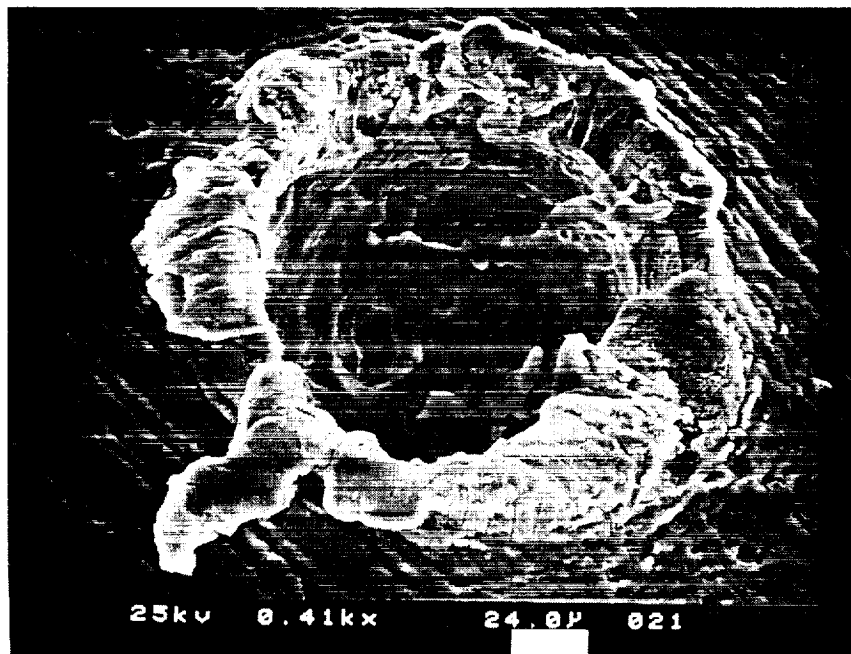
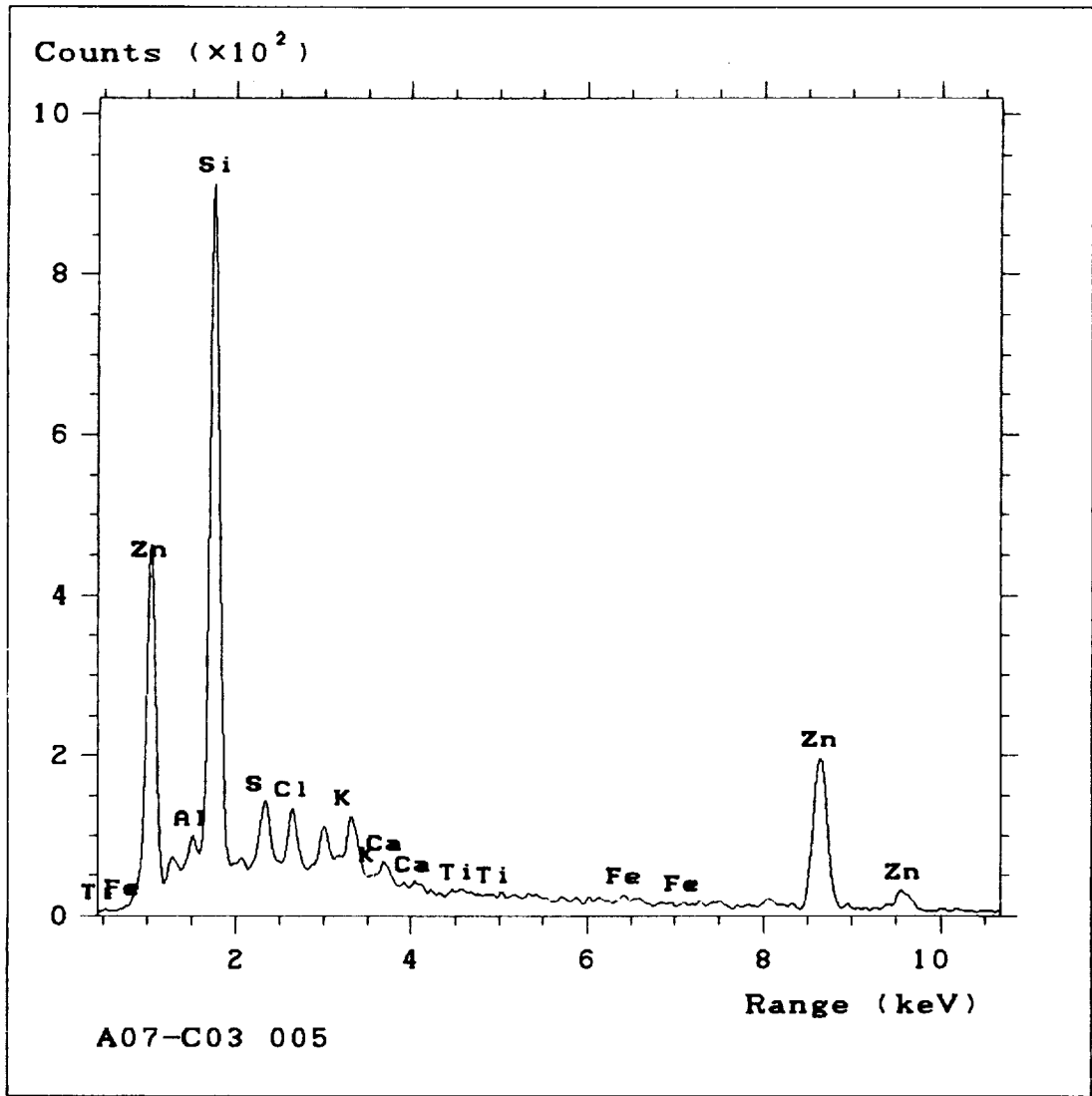
CLAMP NUMBER A07 CO3

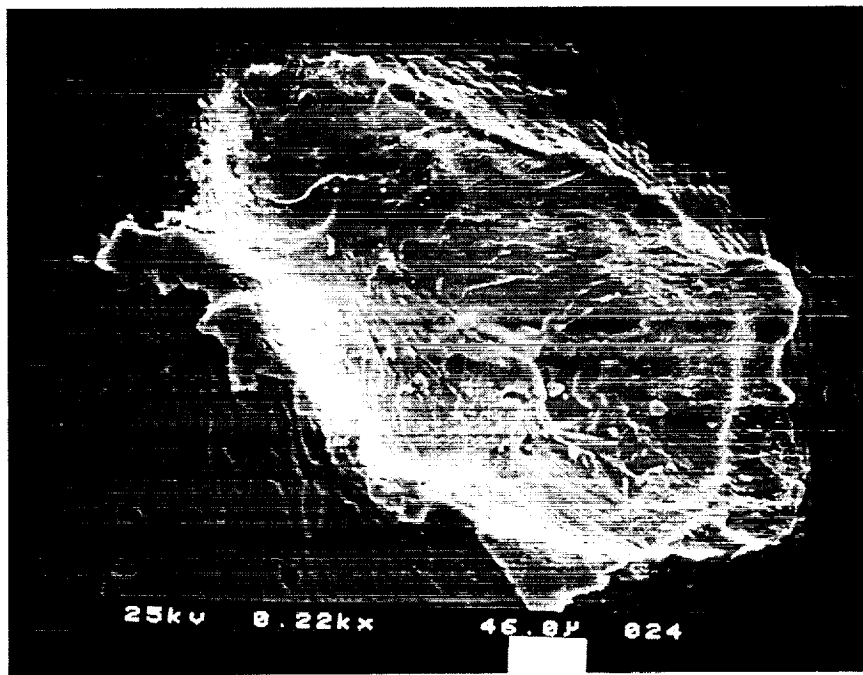
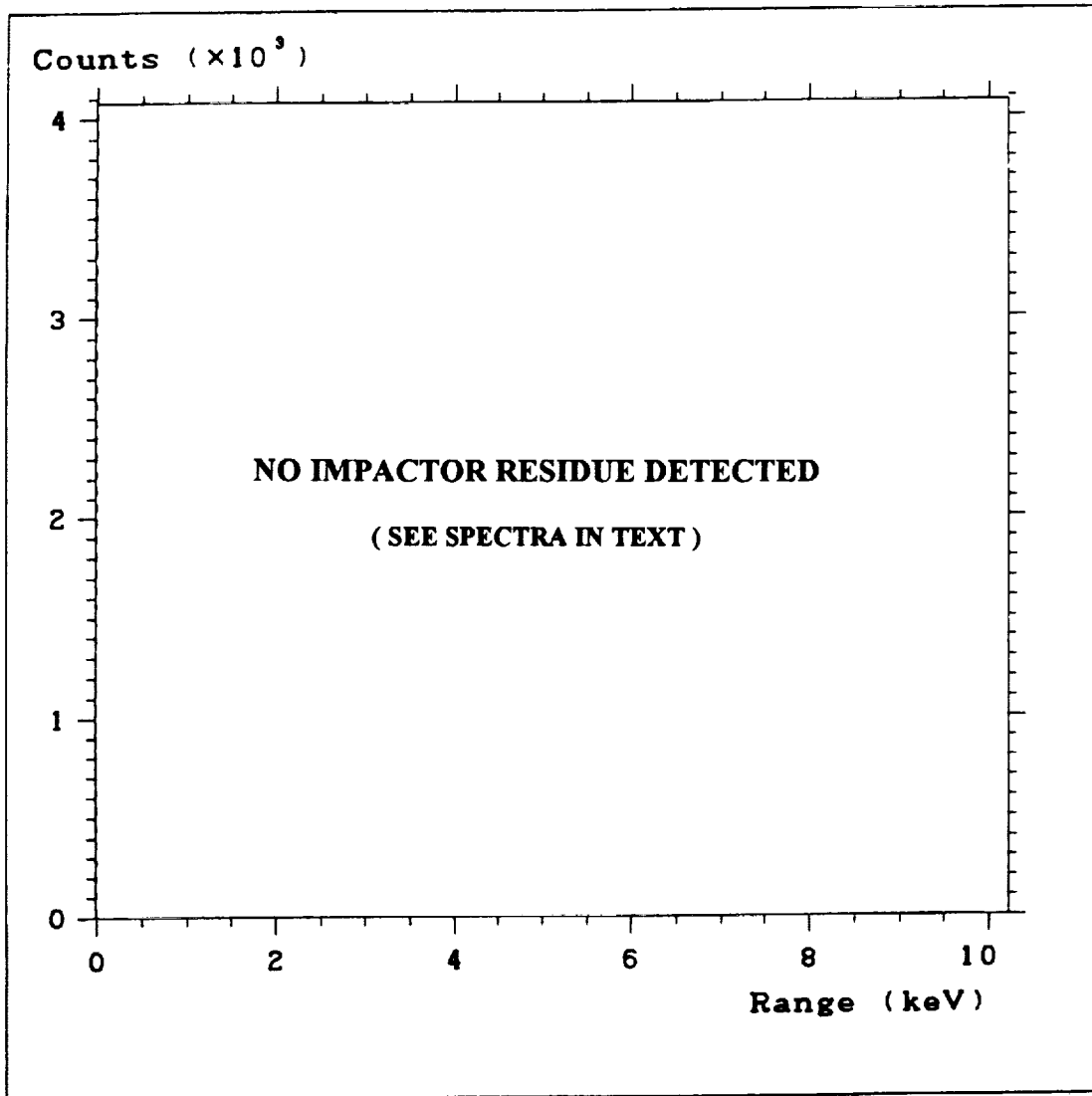
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	380	Unkown
002	260	Contamination
003	N/A	No Impact
004	40	Unkown
005	180	Paint
006	400	Unkown
007	40	Contamination

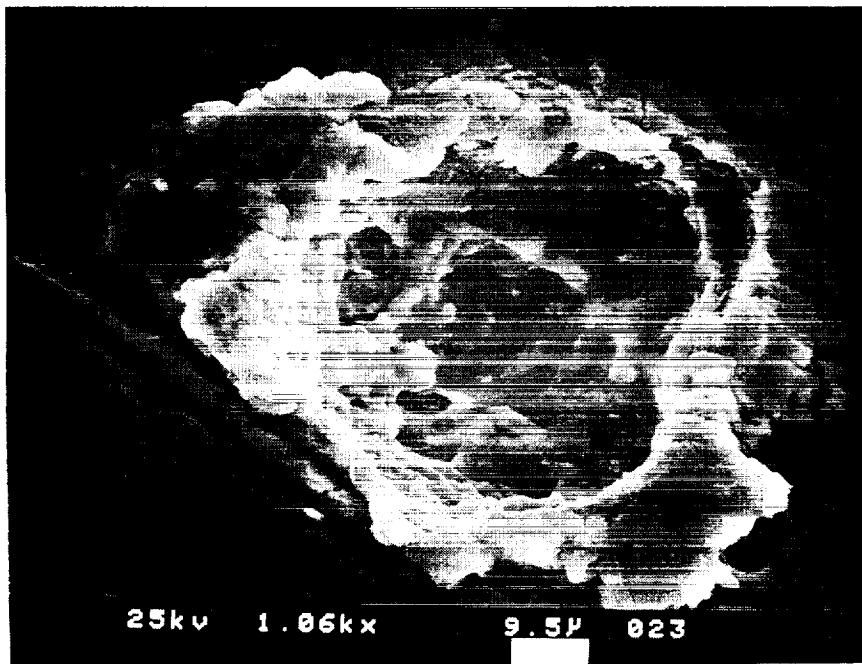
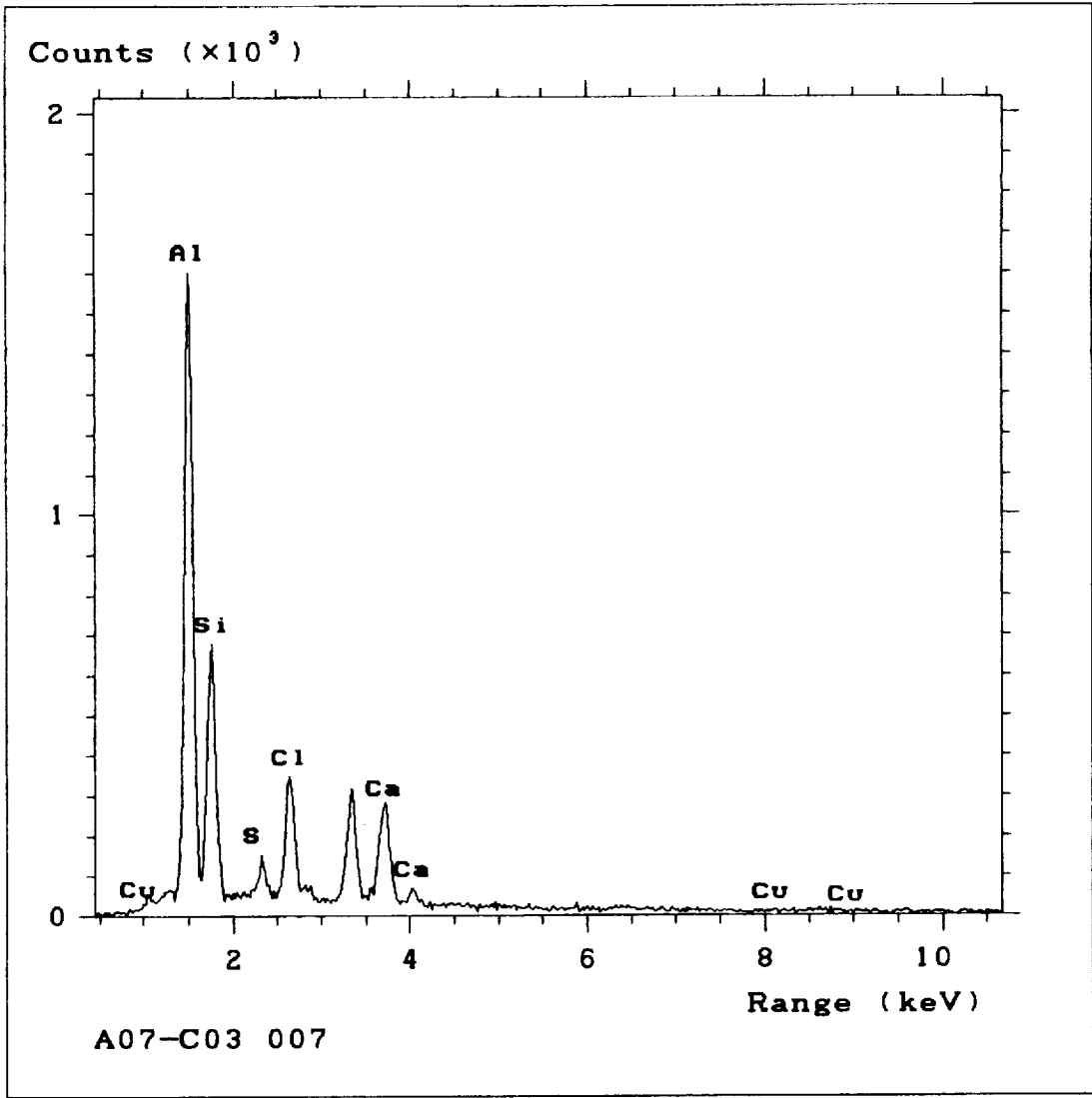






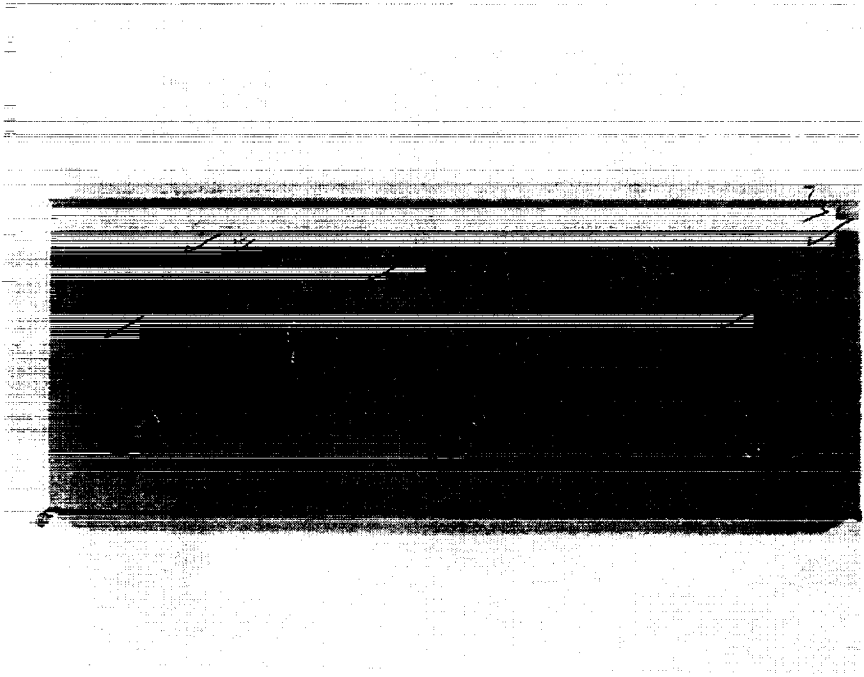


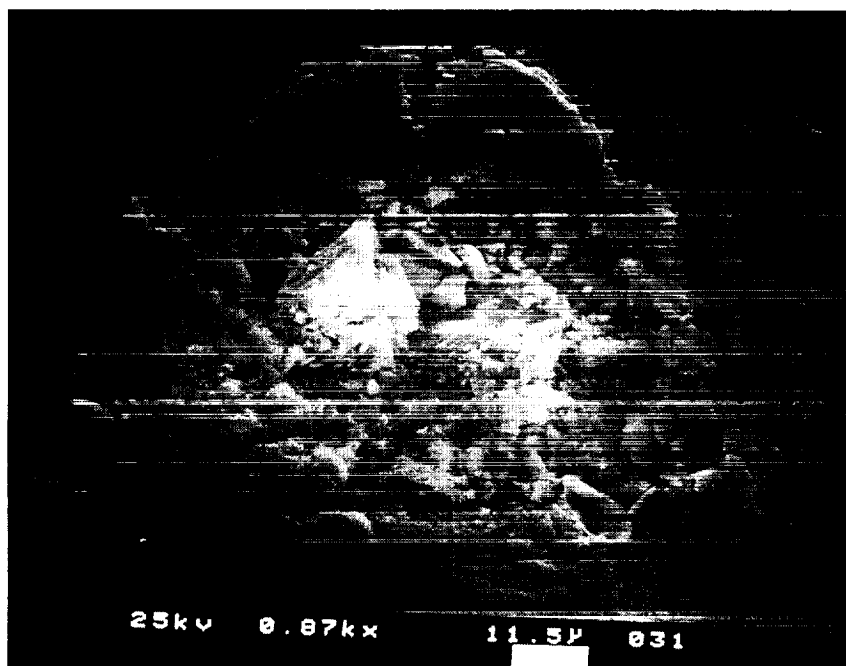
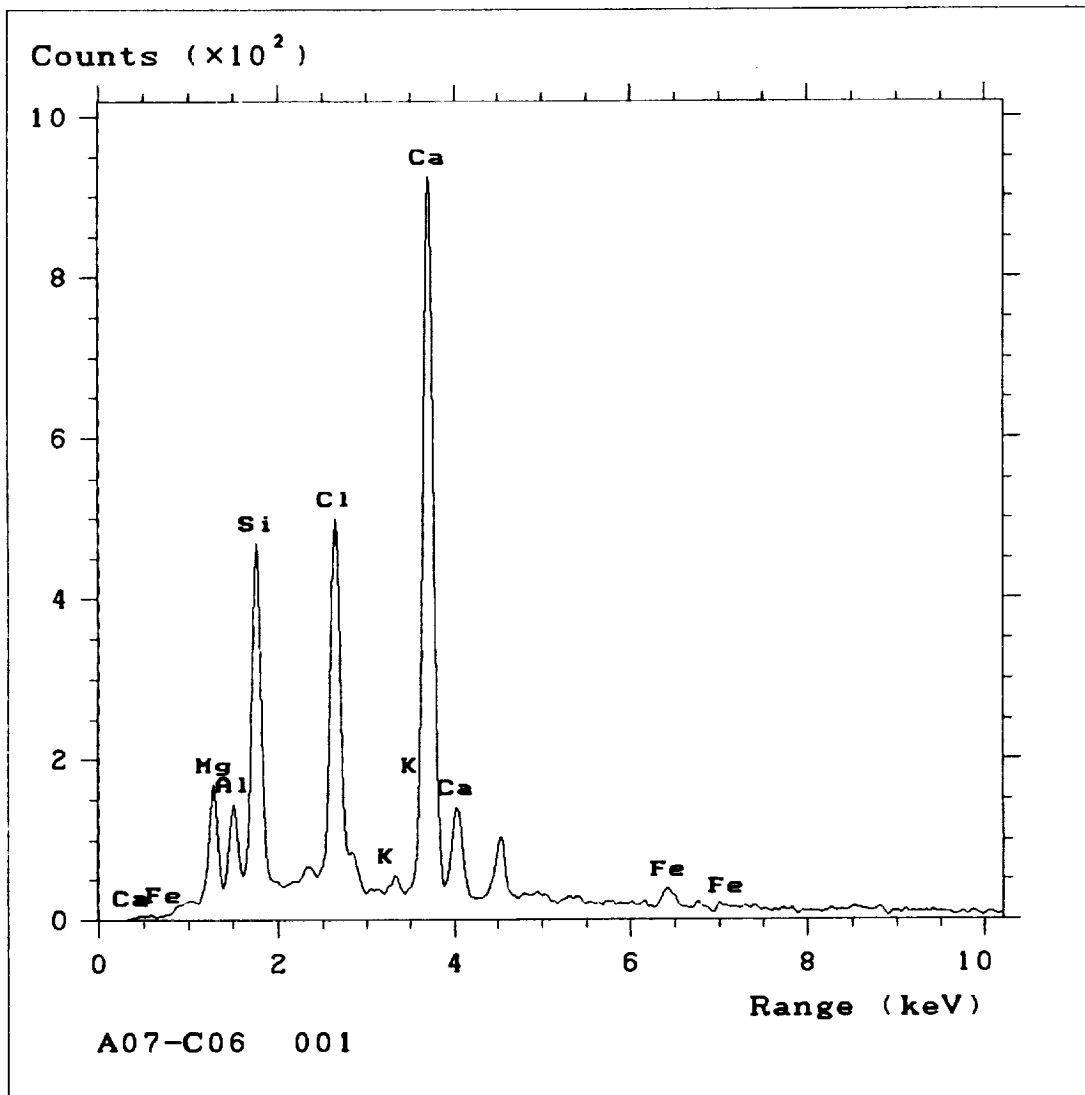


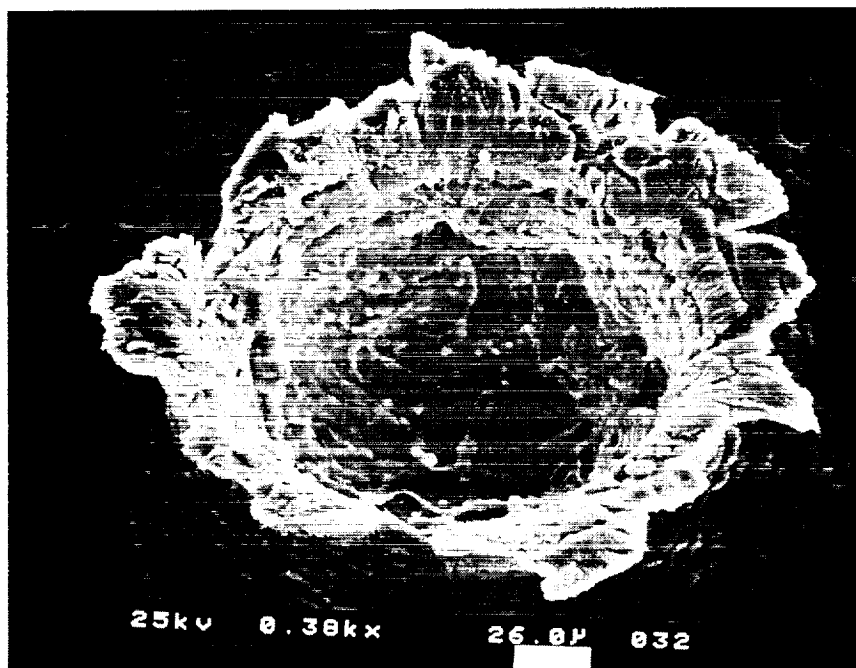
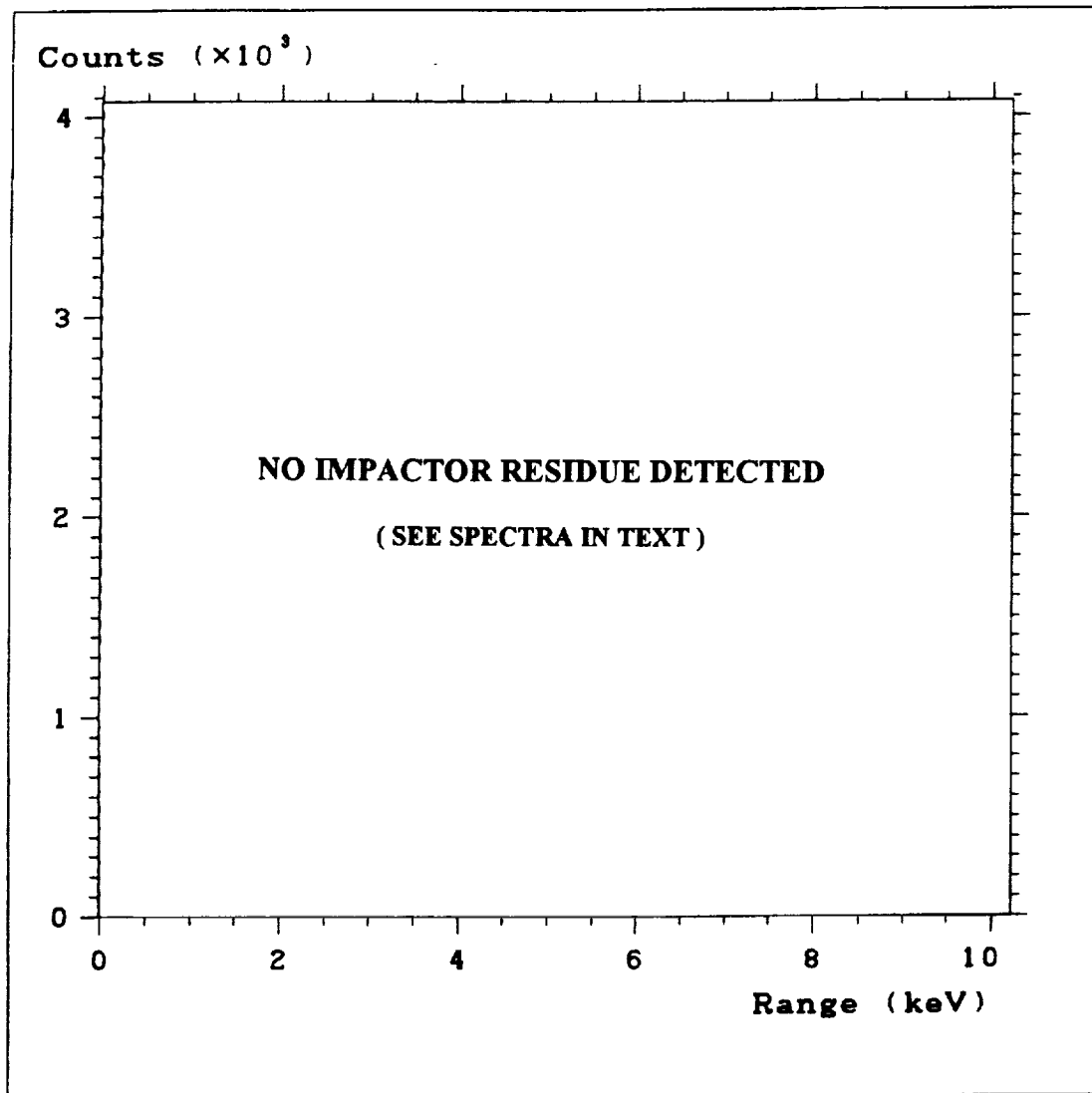


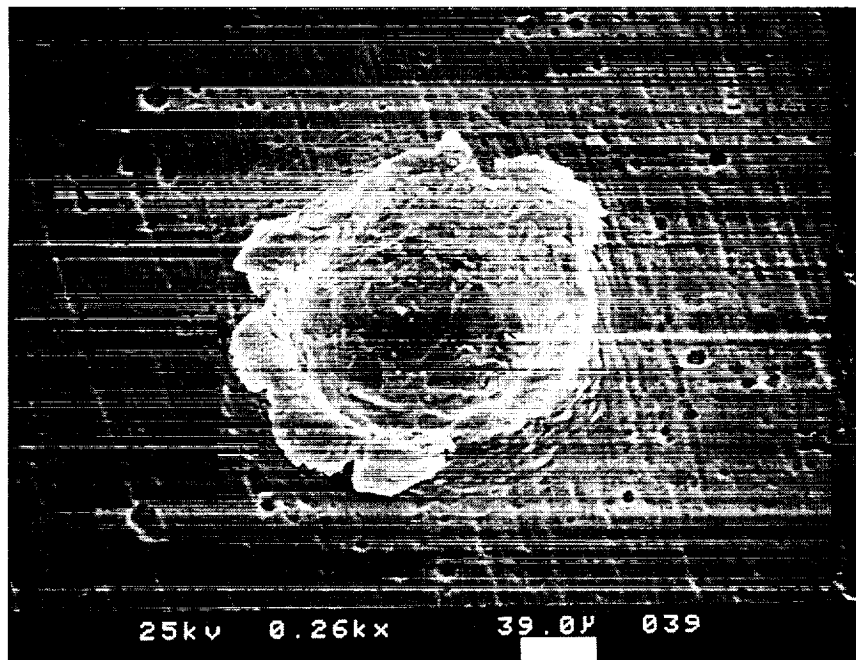
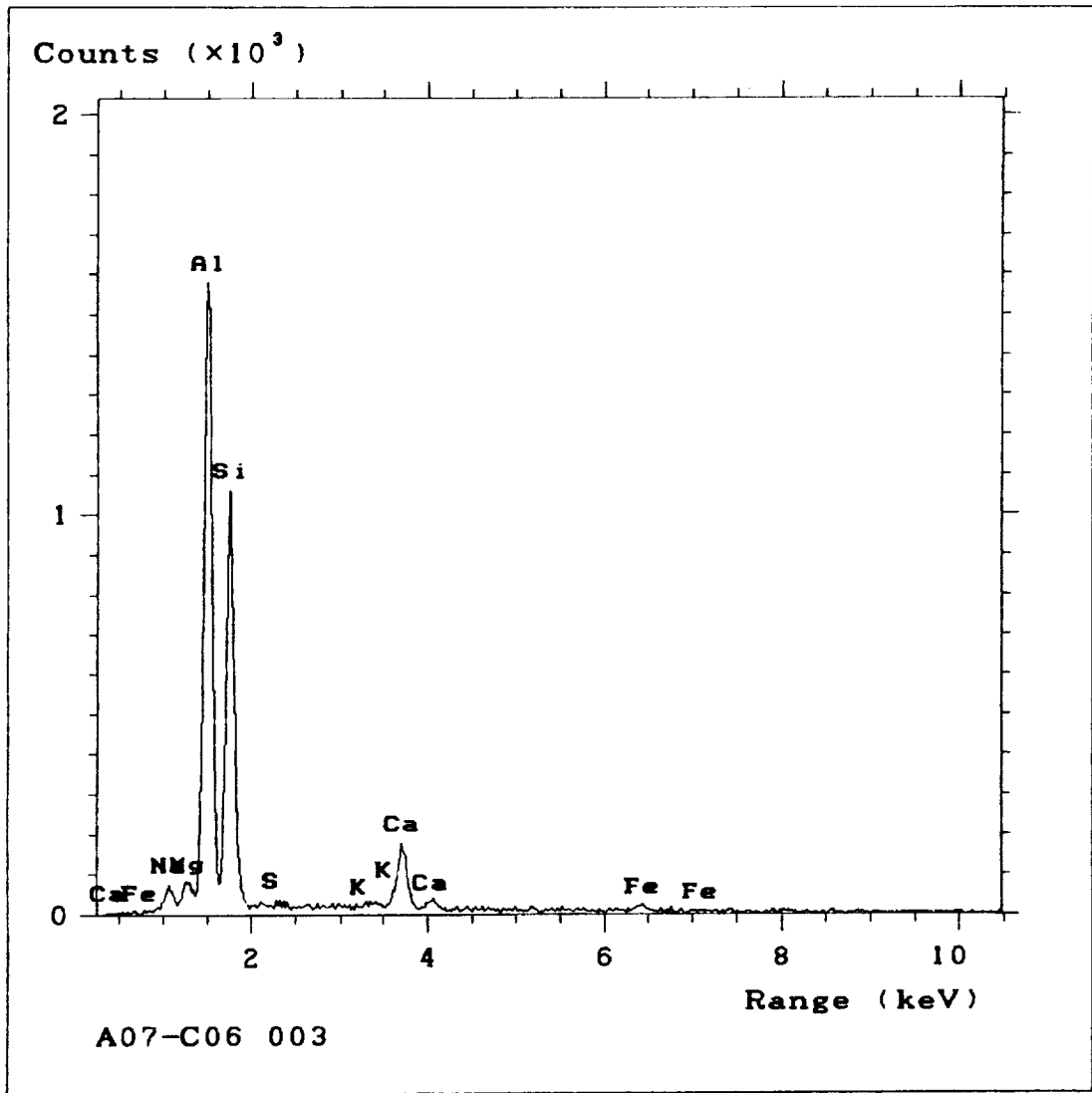
CLAMP NUMBER A07 CO6

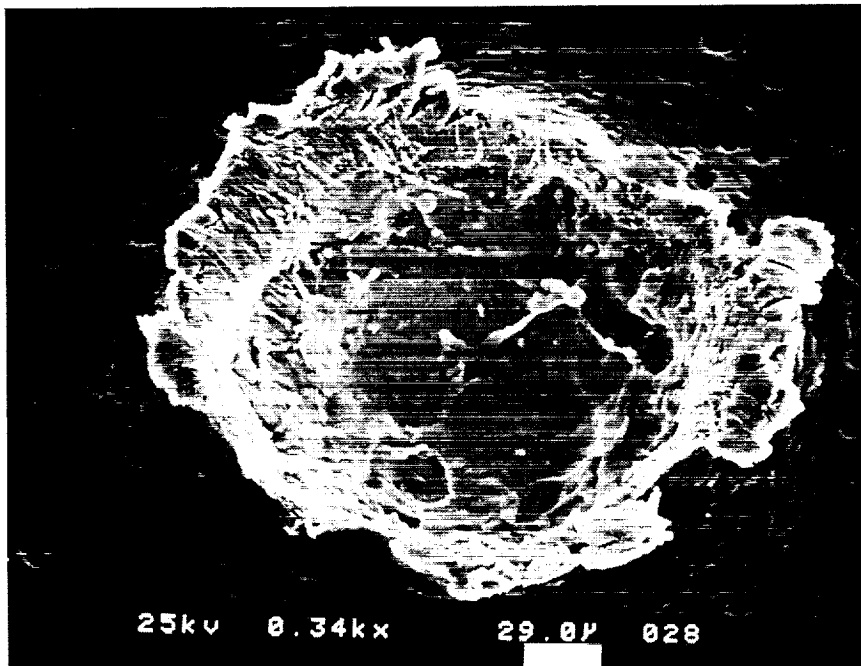
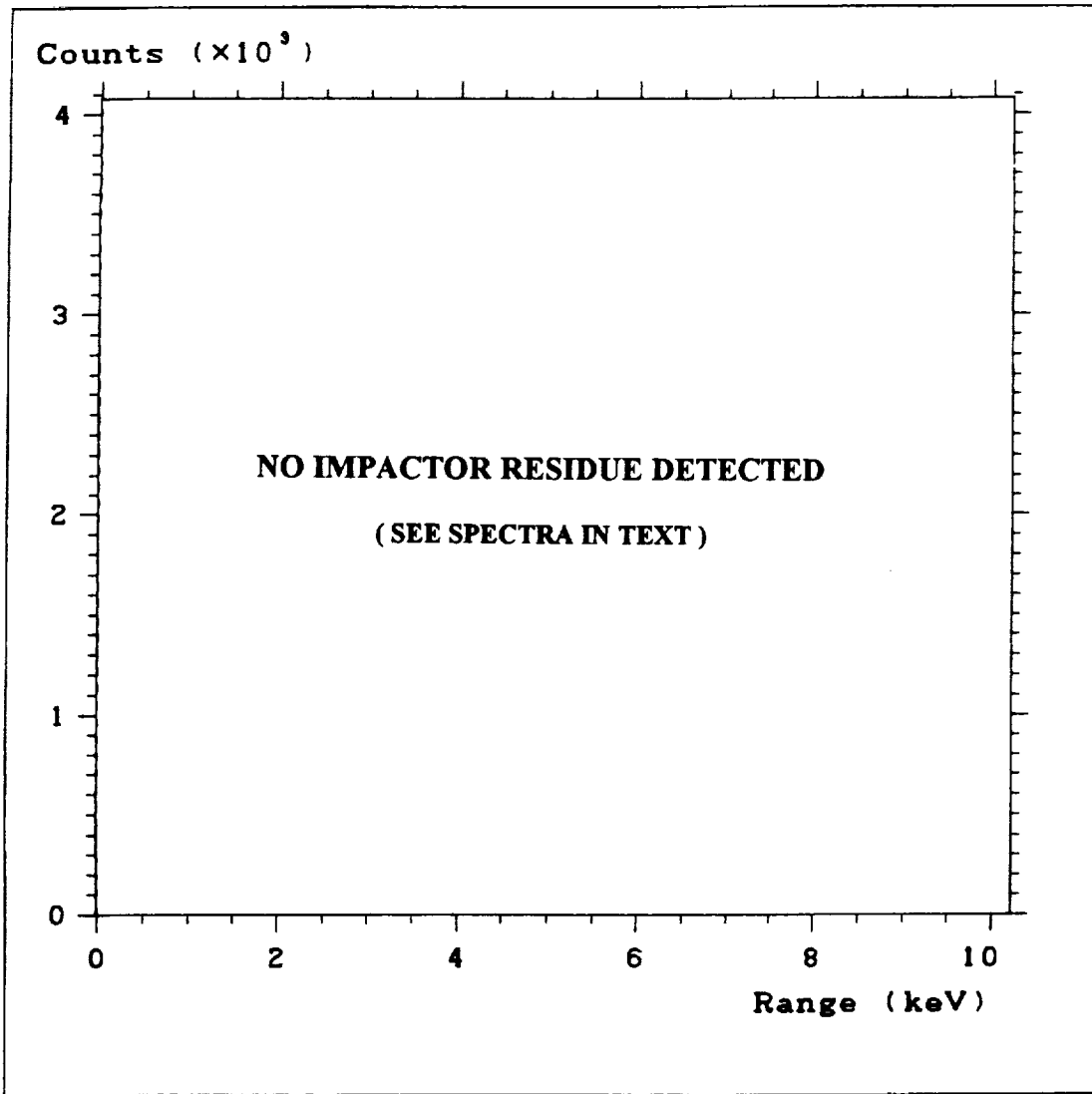
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	100	Contamination
002	220	Unkown
003	200	Si, Ca, Na, Mg, Fe
004	240	Unkown
005	100	Fe, Ni, Cr
006	150	Unkown
007	300	Trace
008	150	Unkown

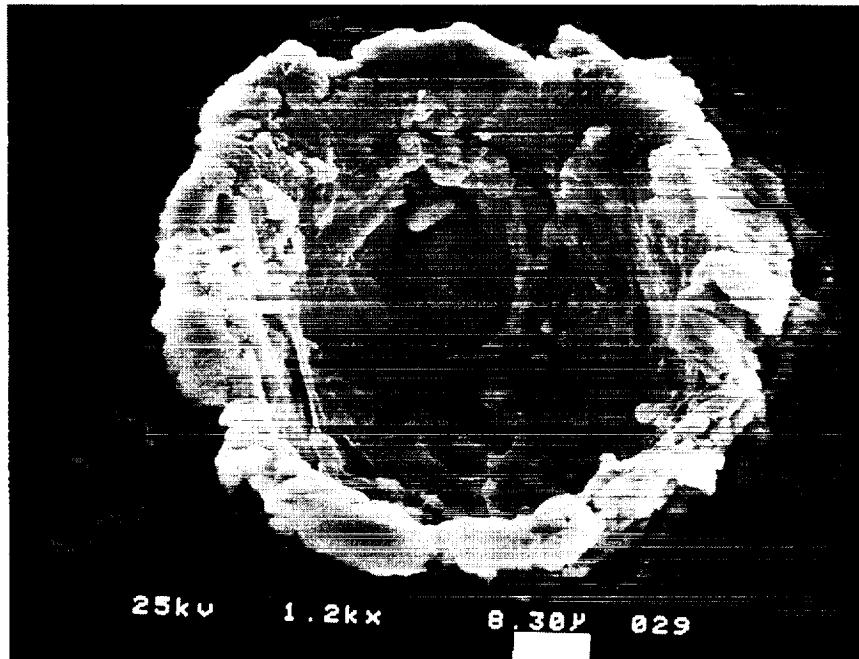
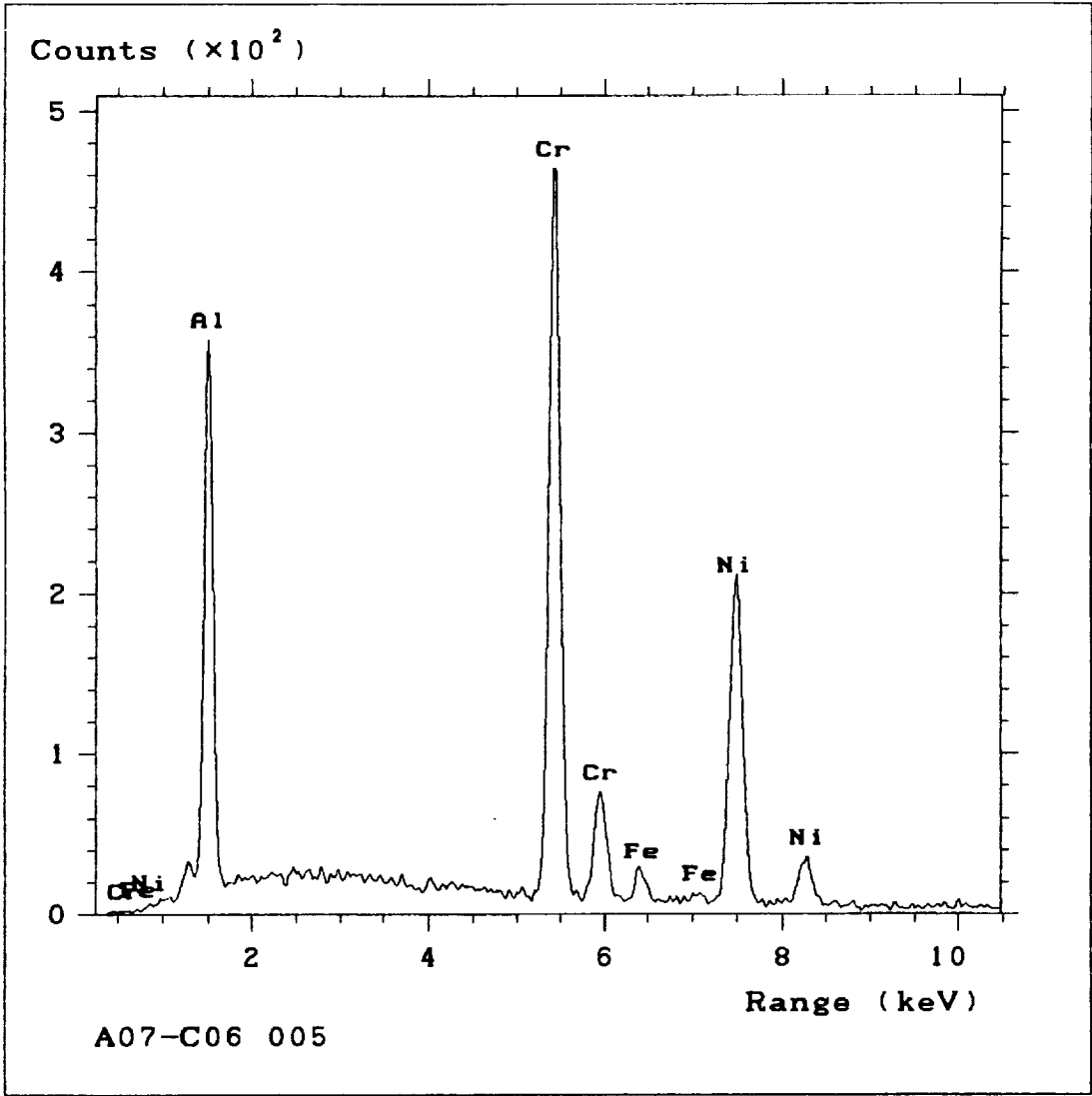


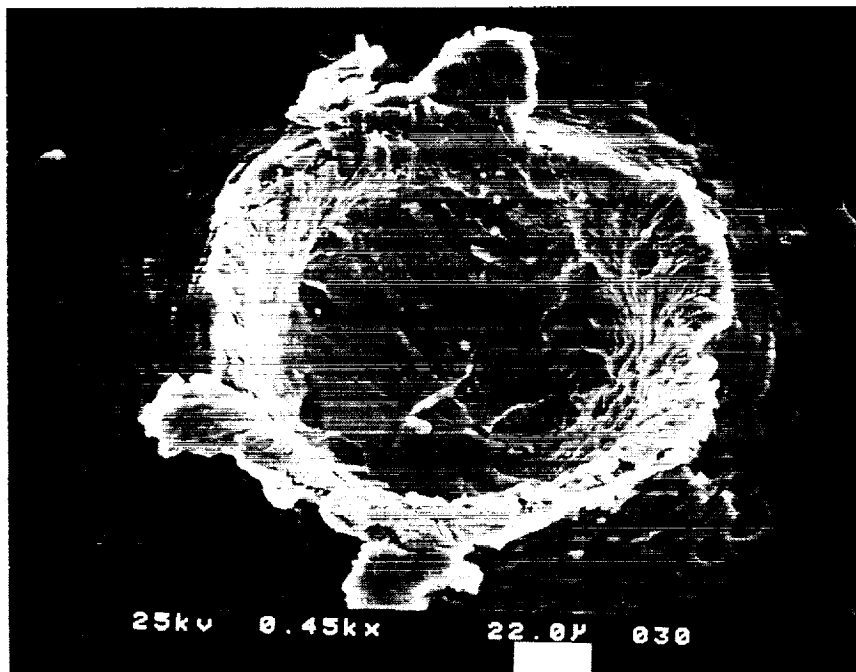
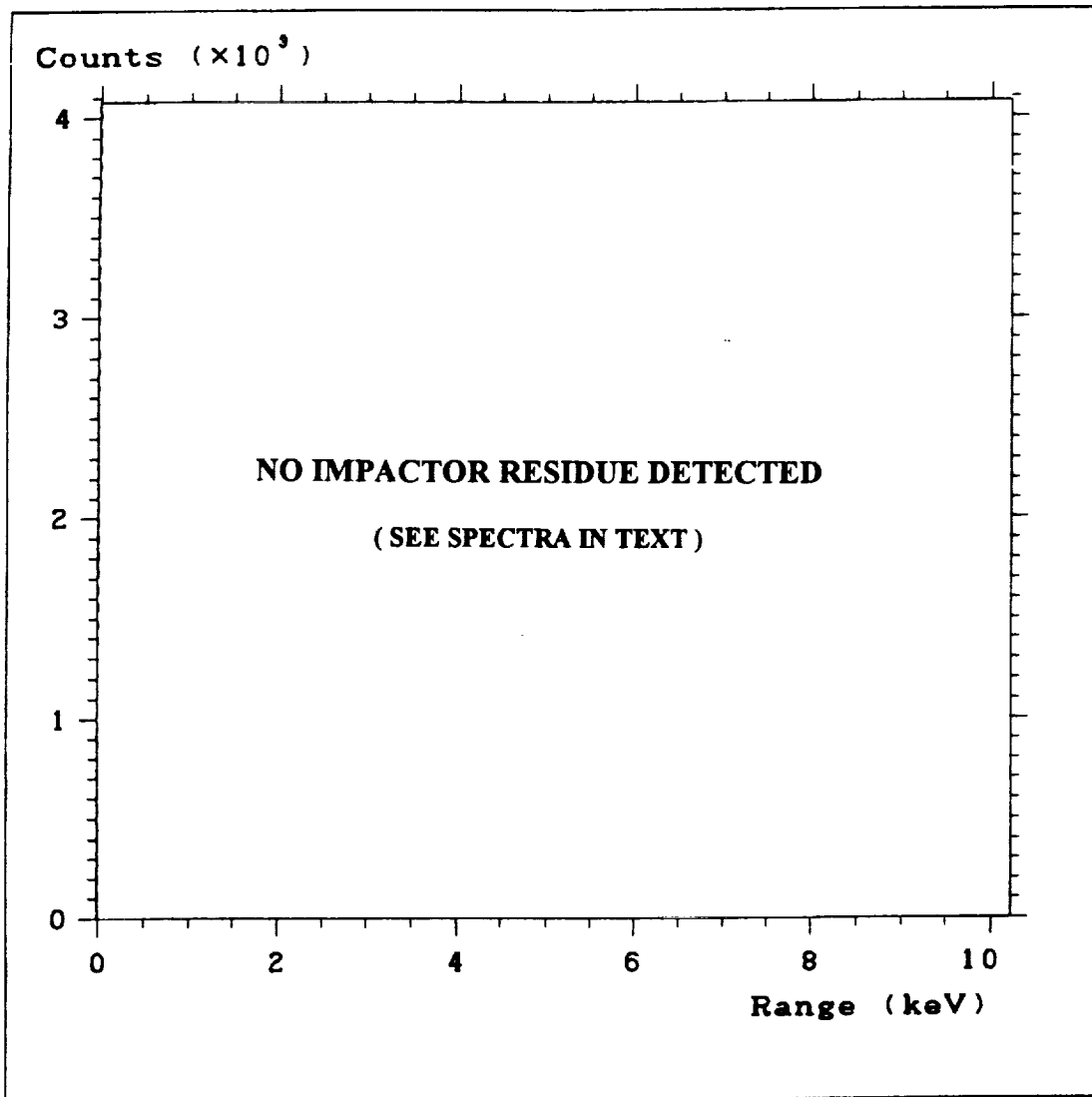


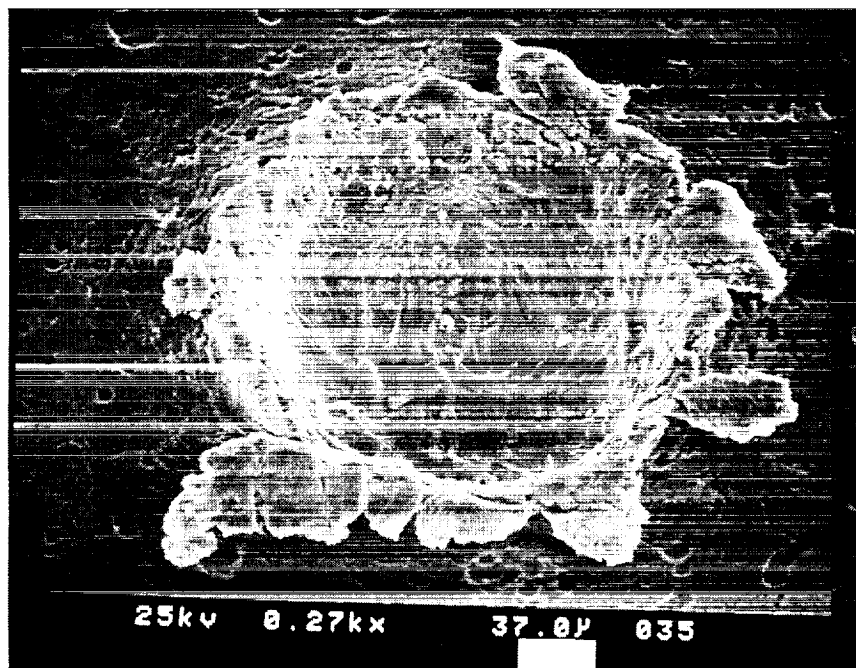
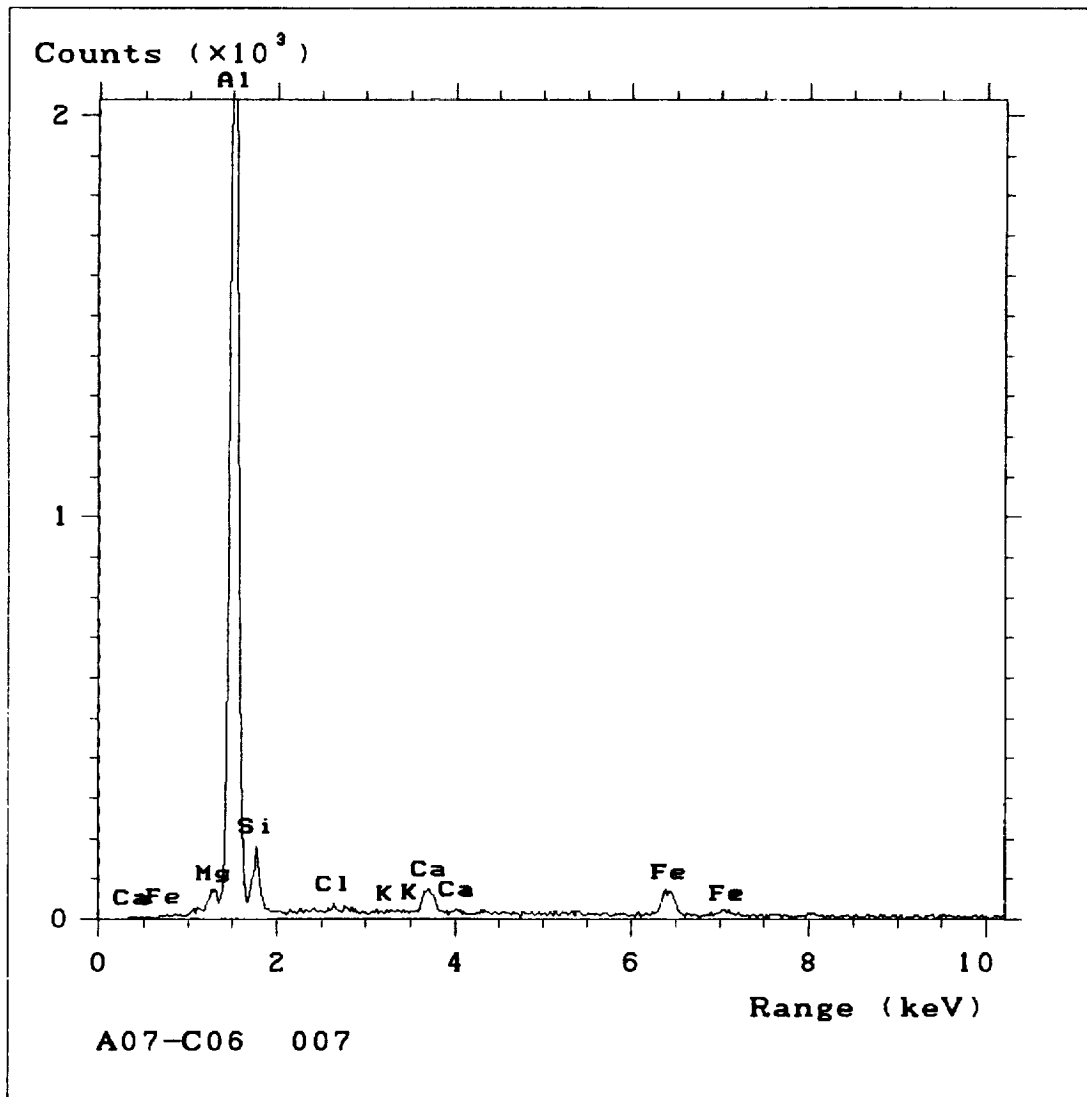


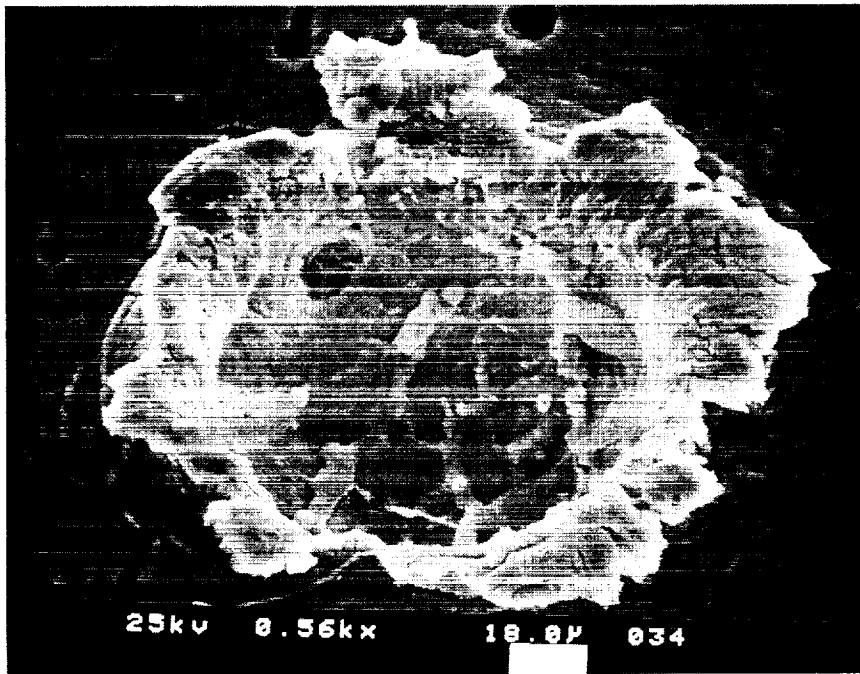
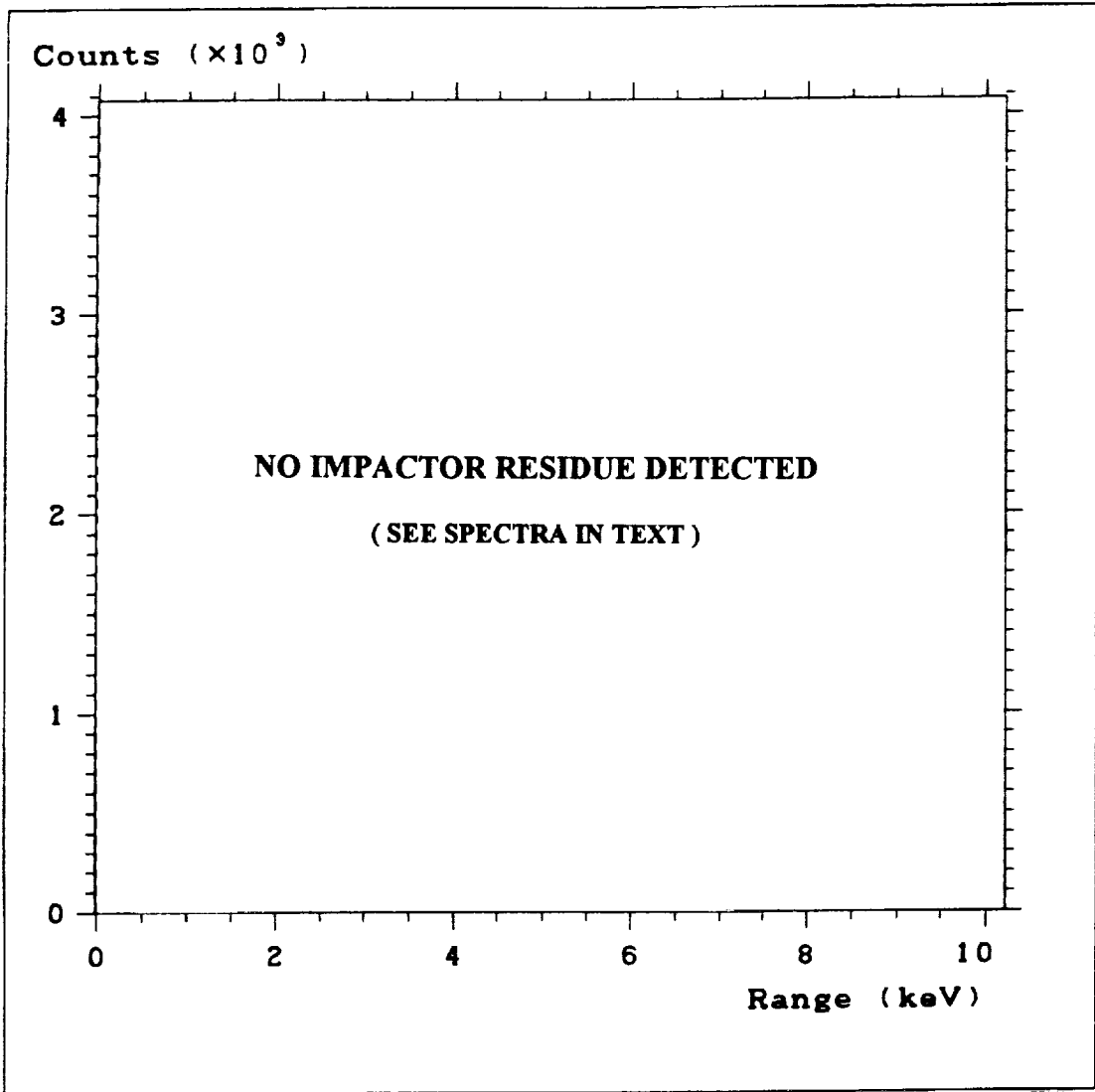






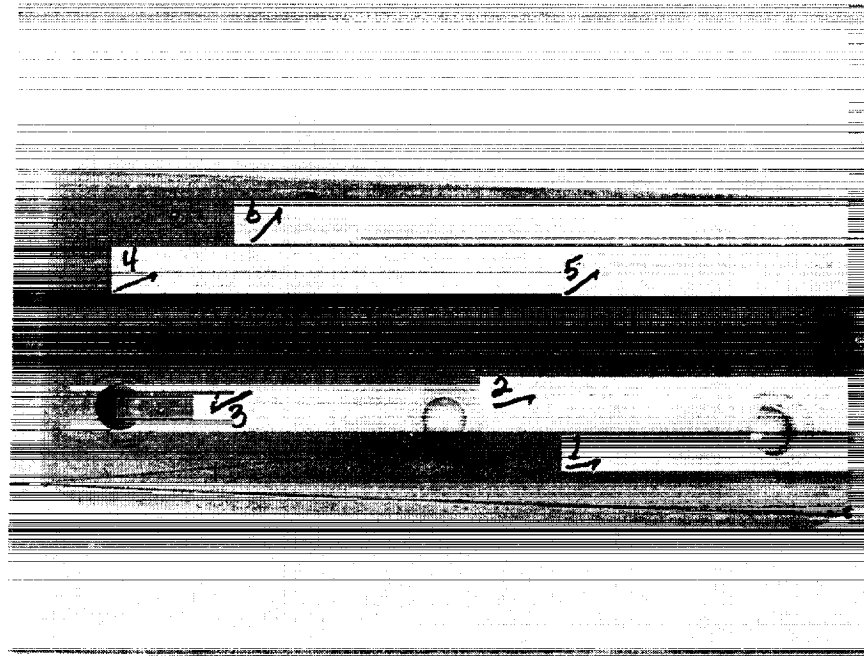


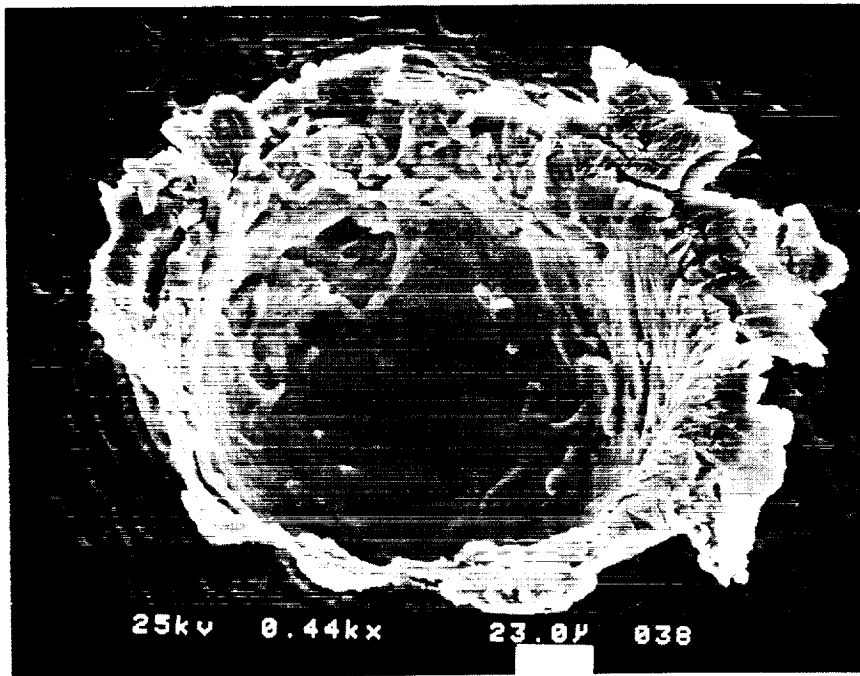
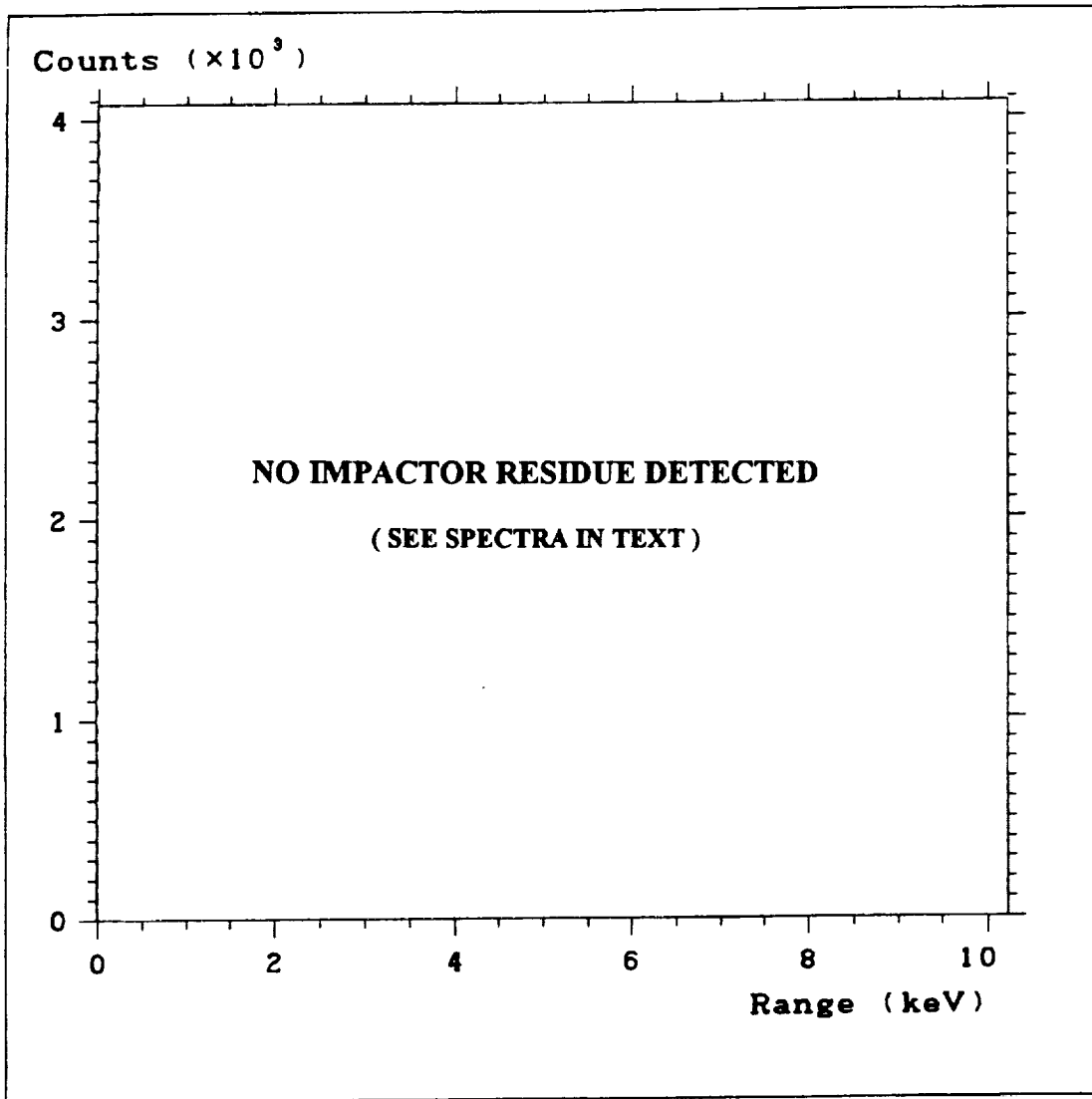


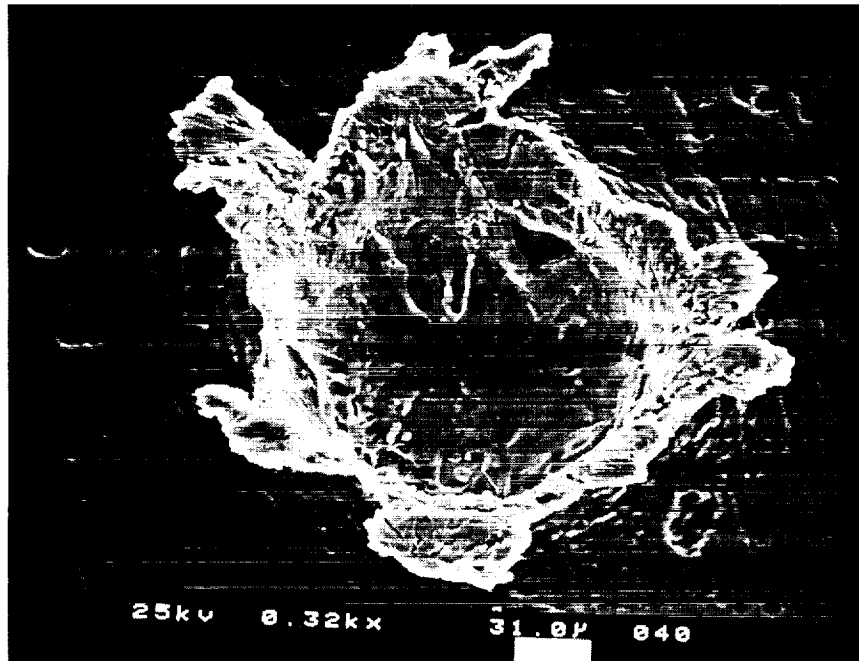
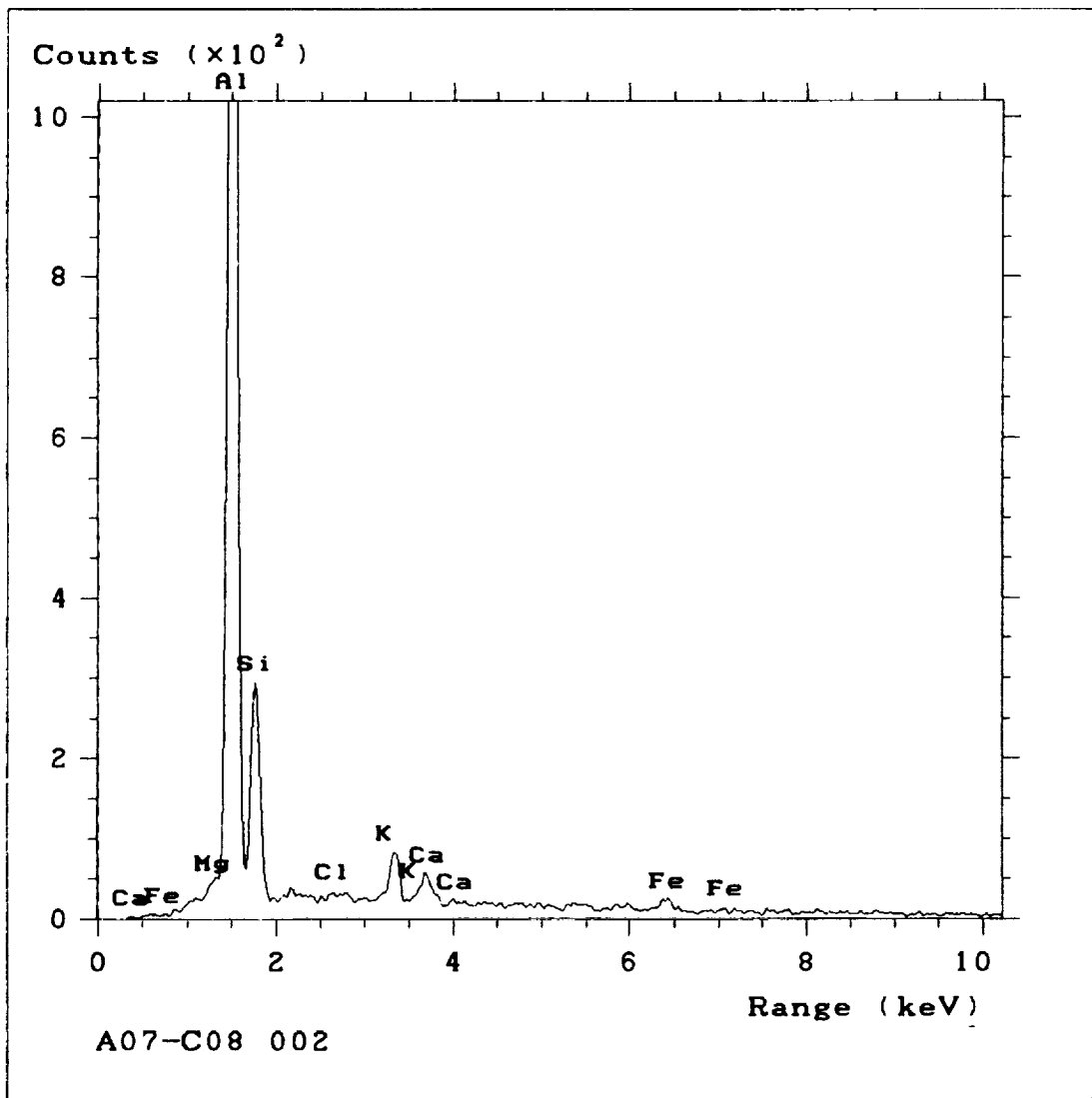


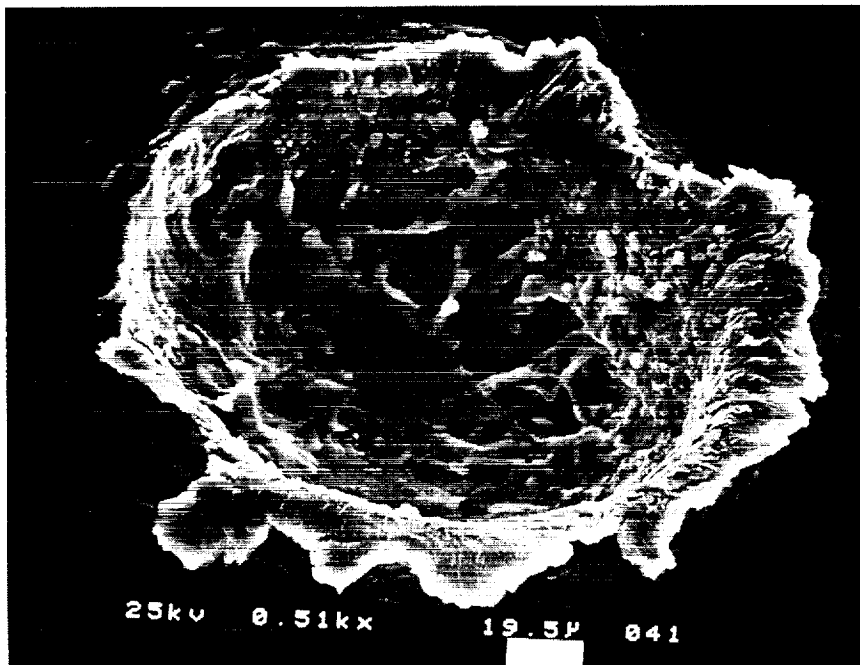
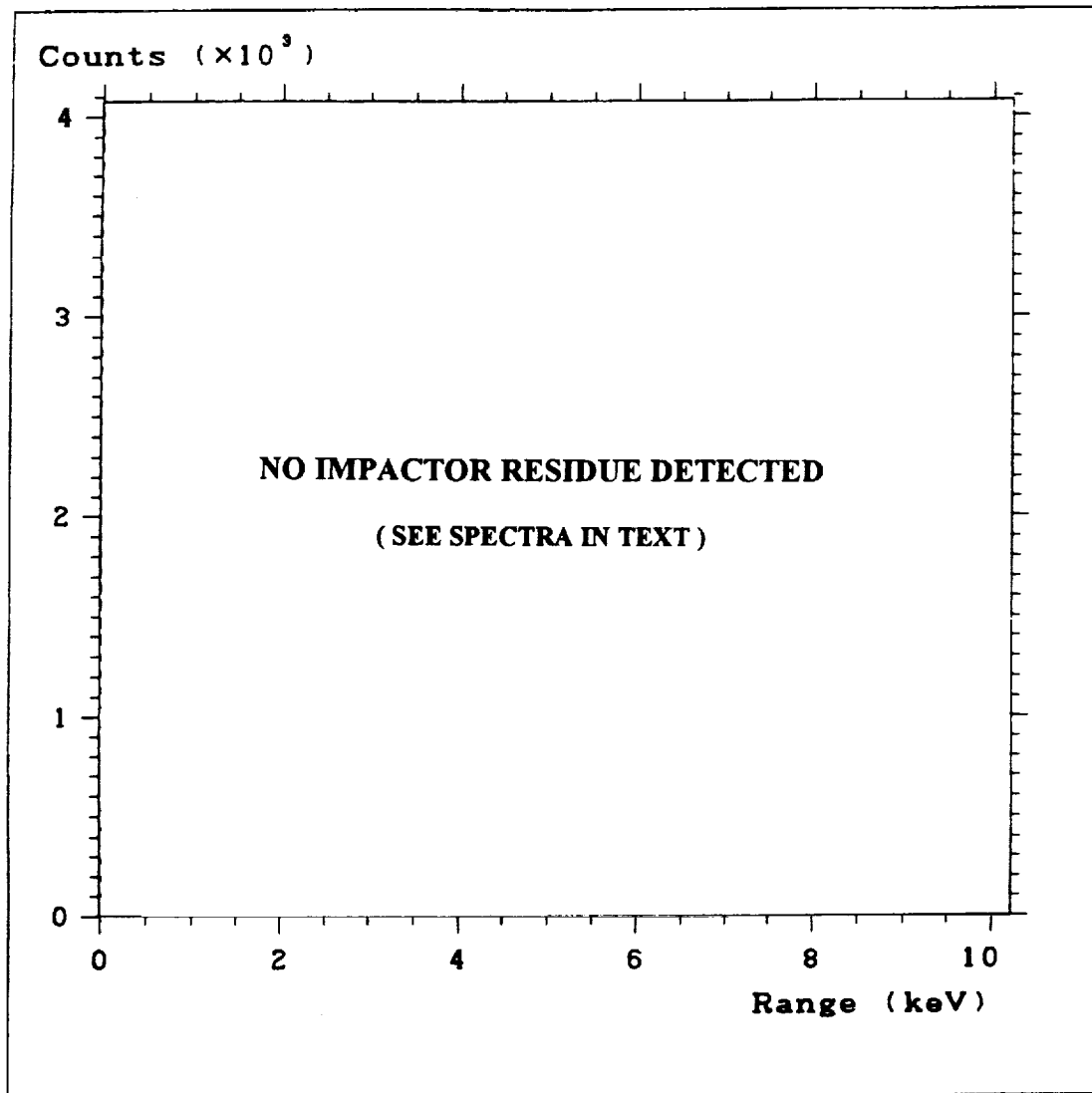
CLAMP NUMBER A07 C08

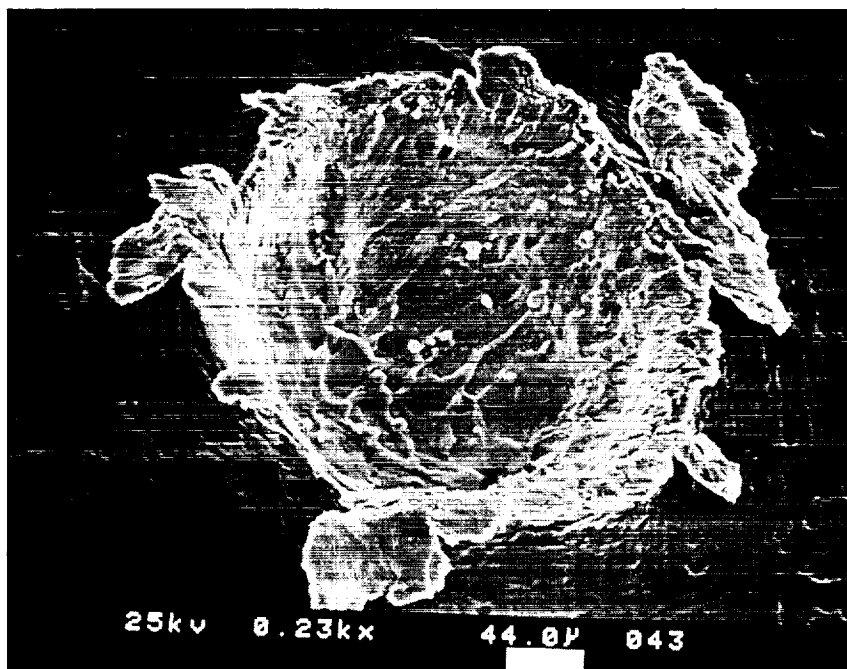
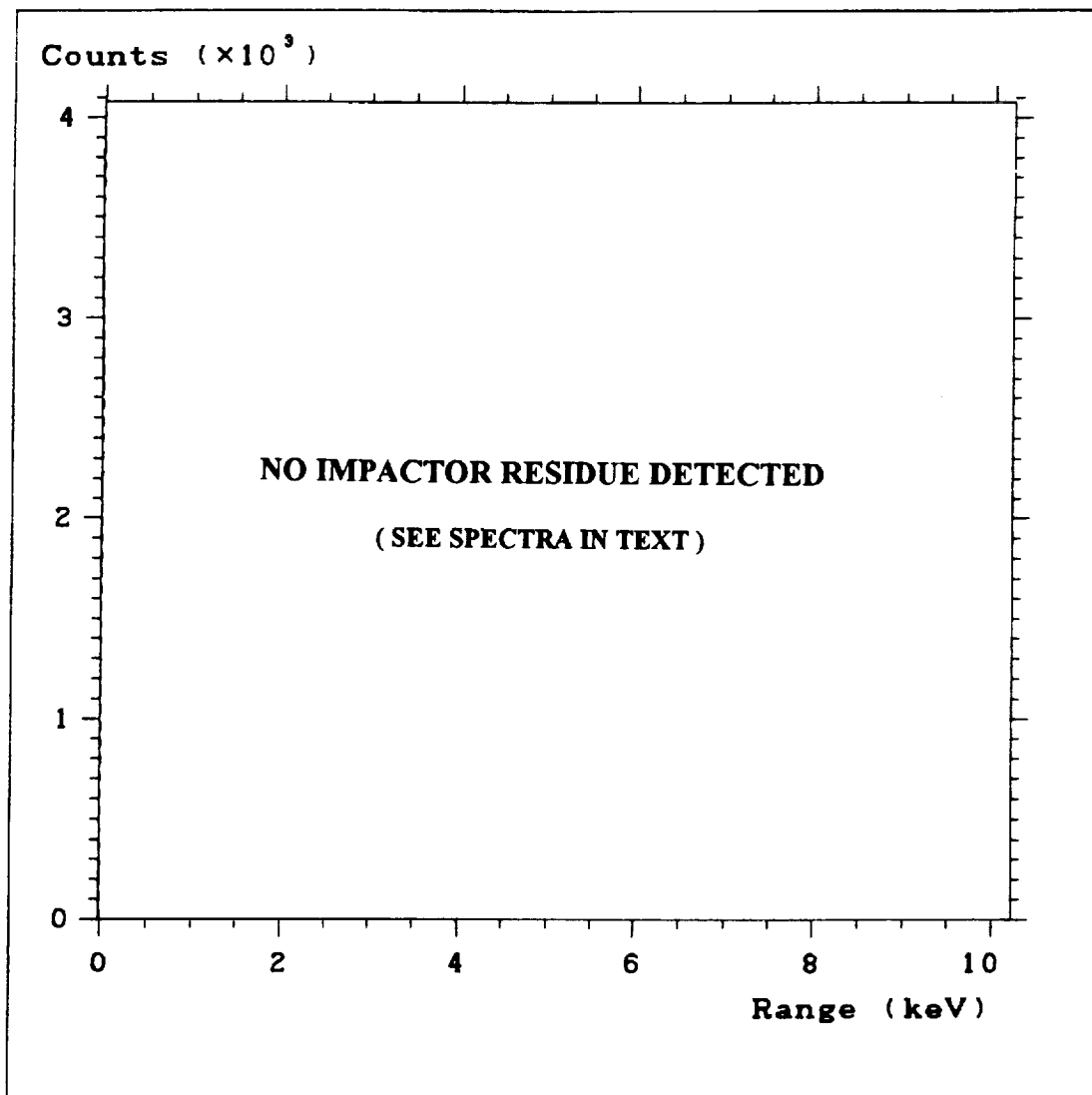
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	200	Unkown
002	220	Trace
003	210	Unkown
004	300	Unkown
005	260	Si, Ca, K, Fe, S, Mg
006	140	Si, Mg, Ca, Fe

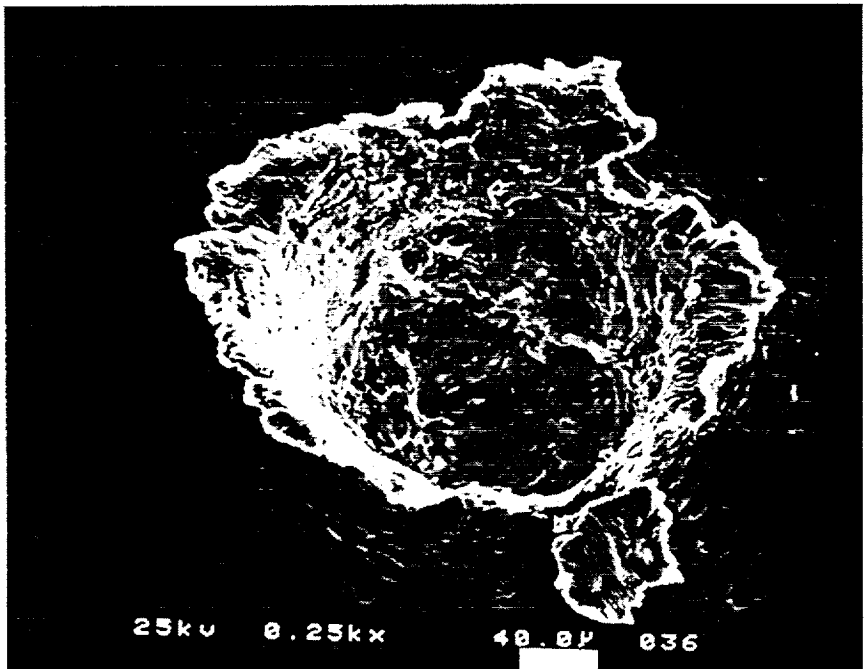
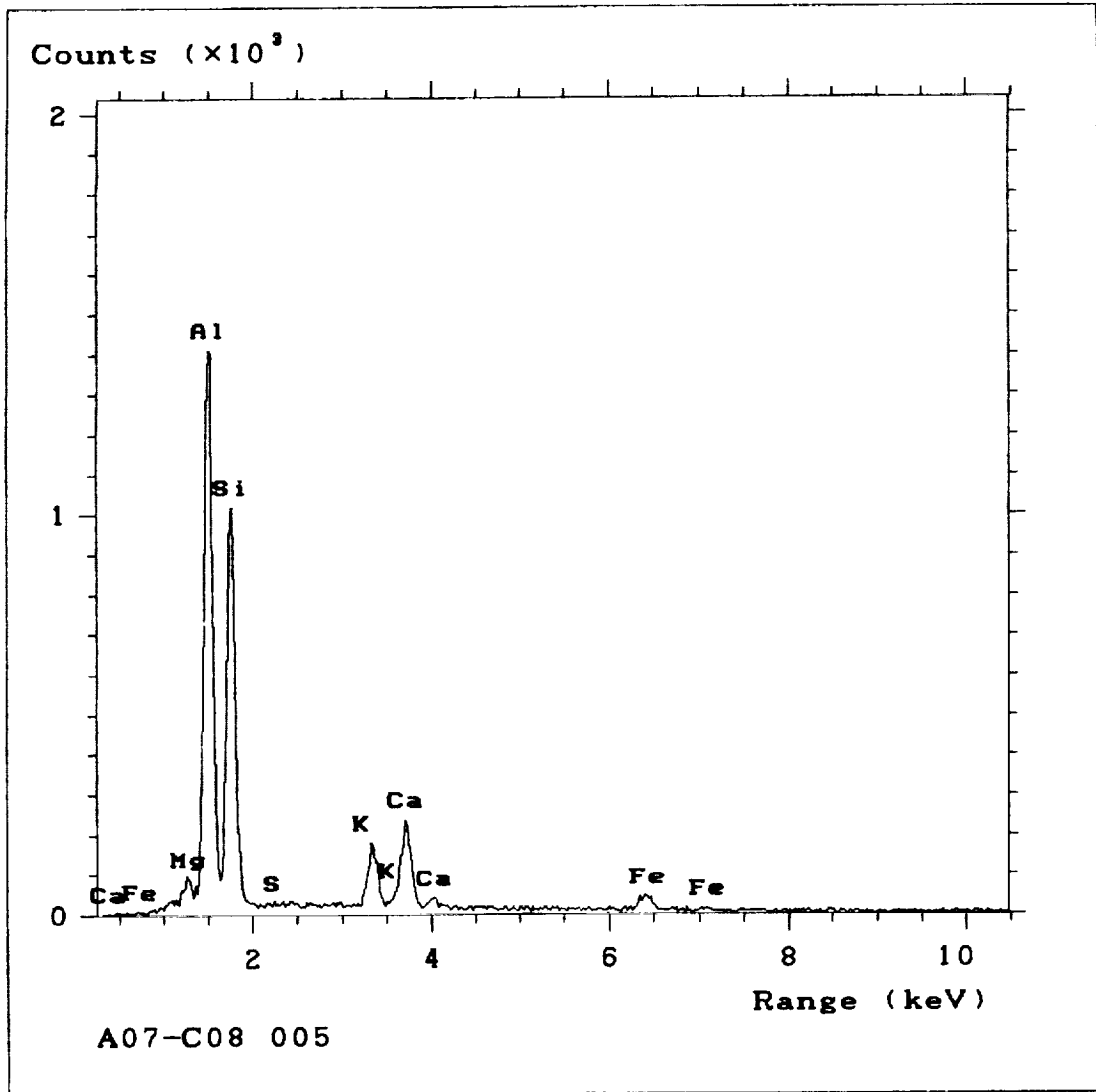


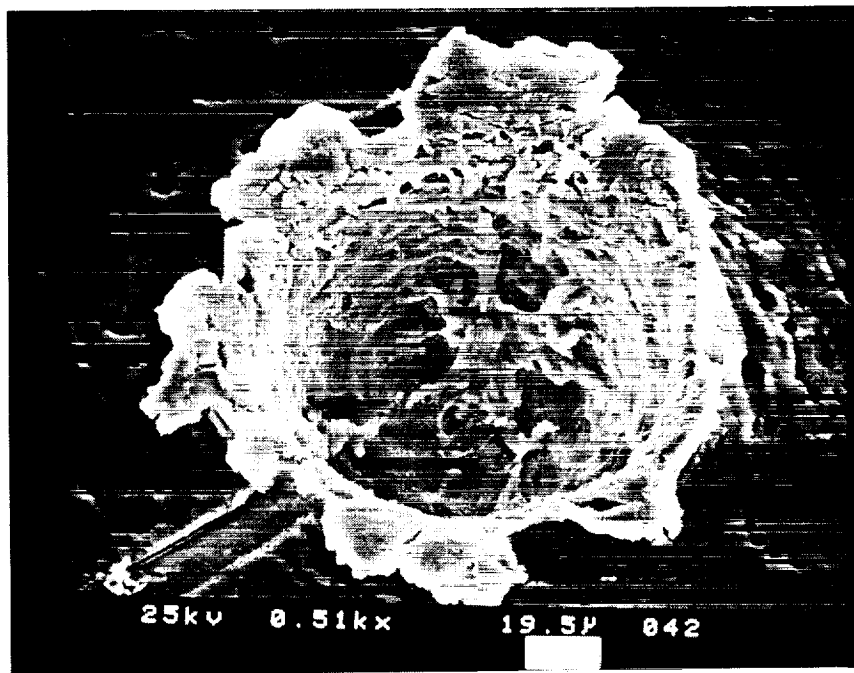
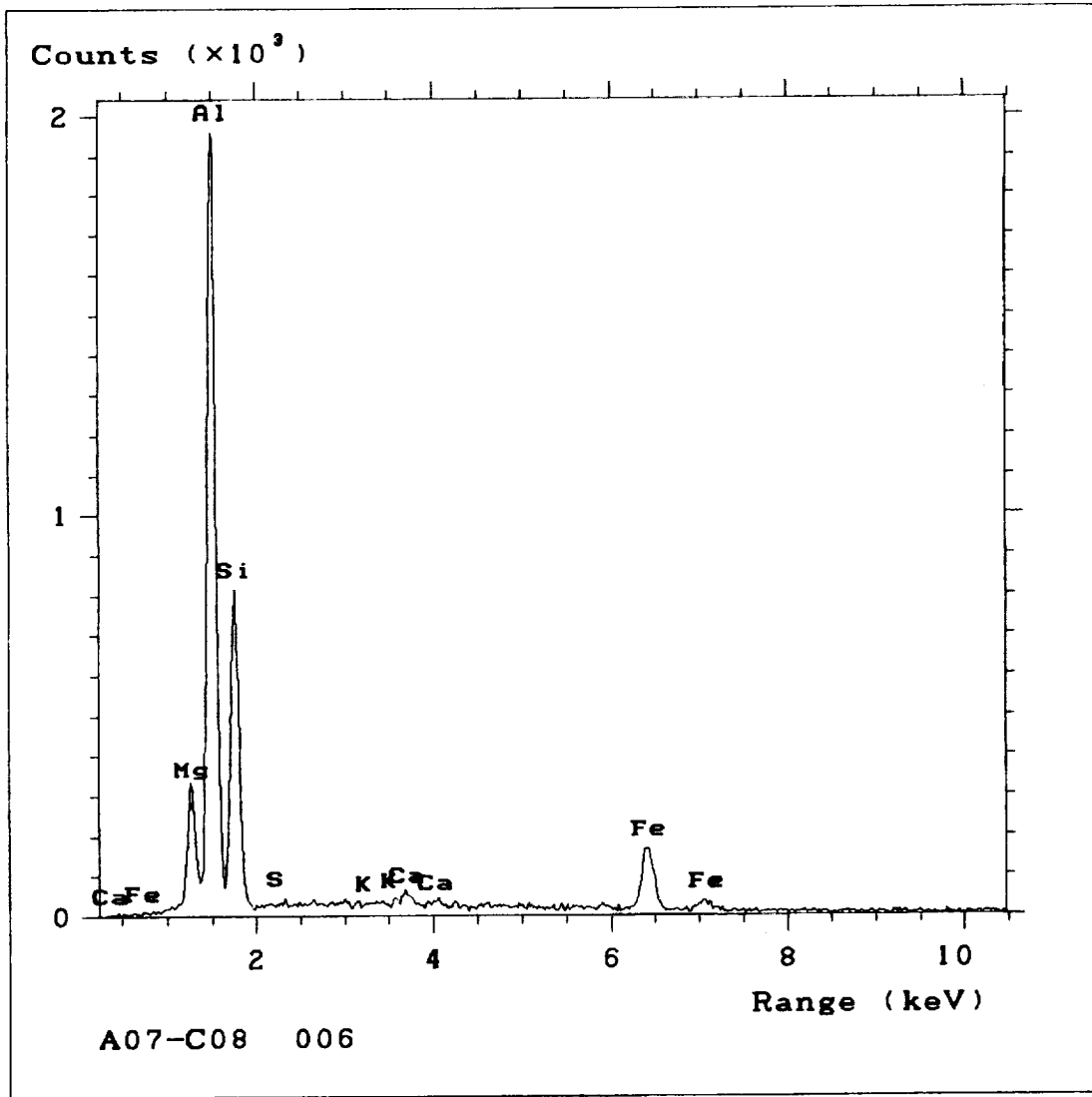






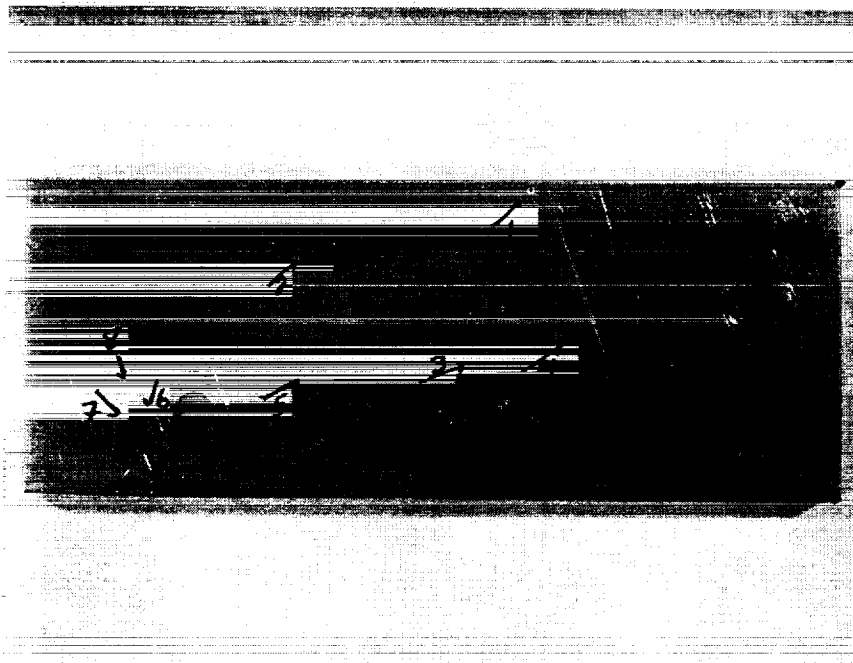


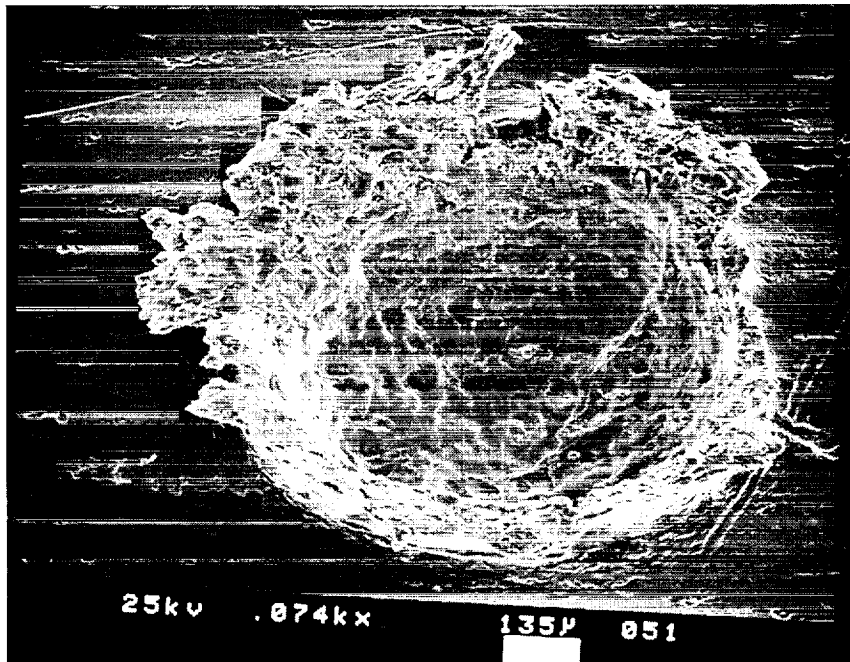
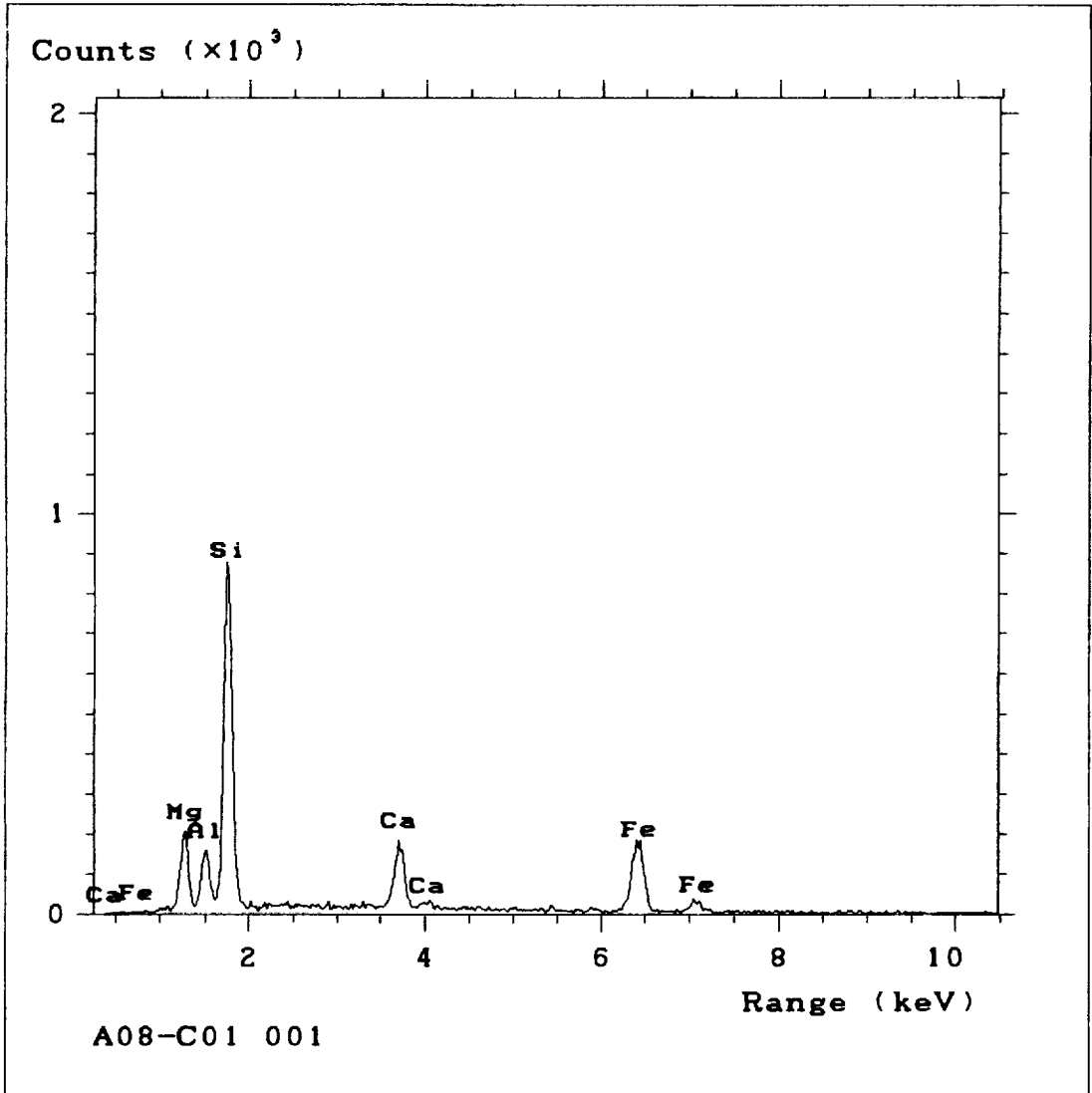


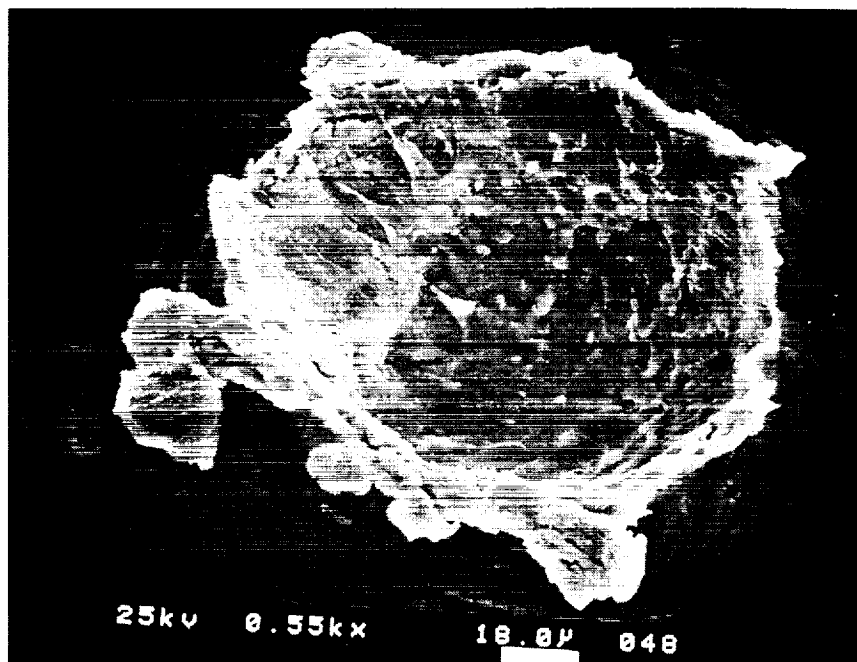
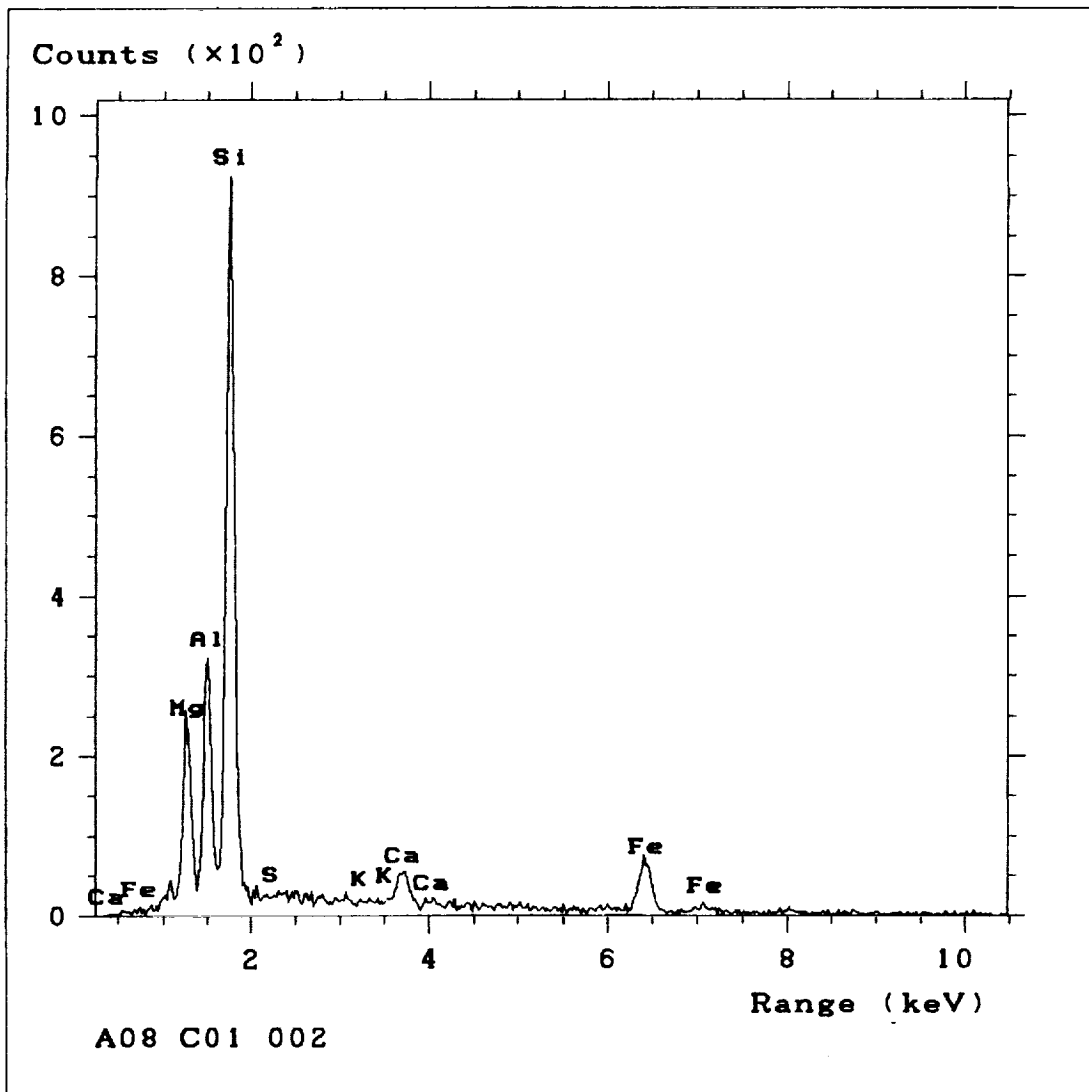


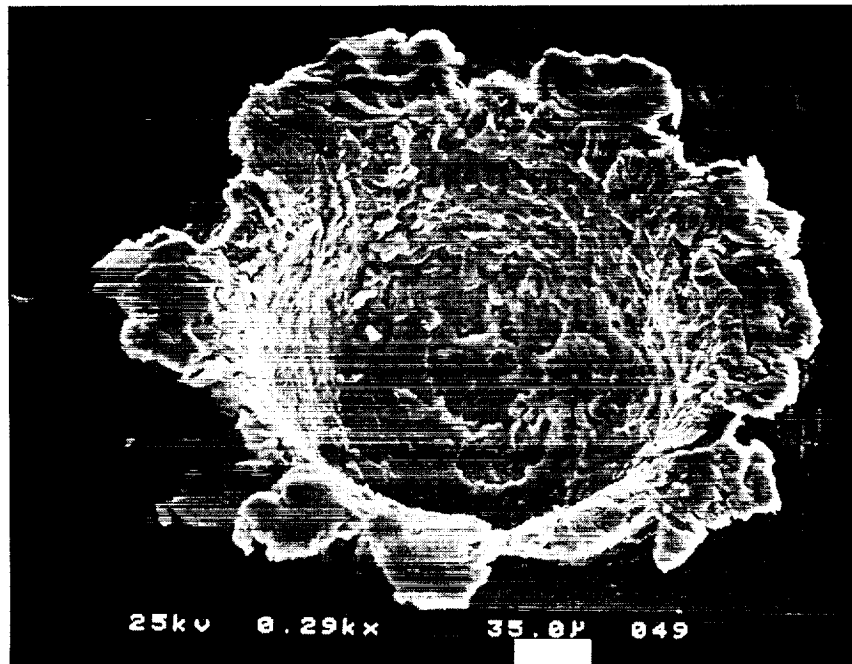
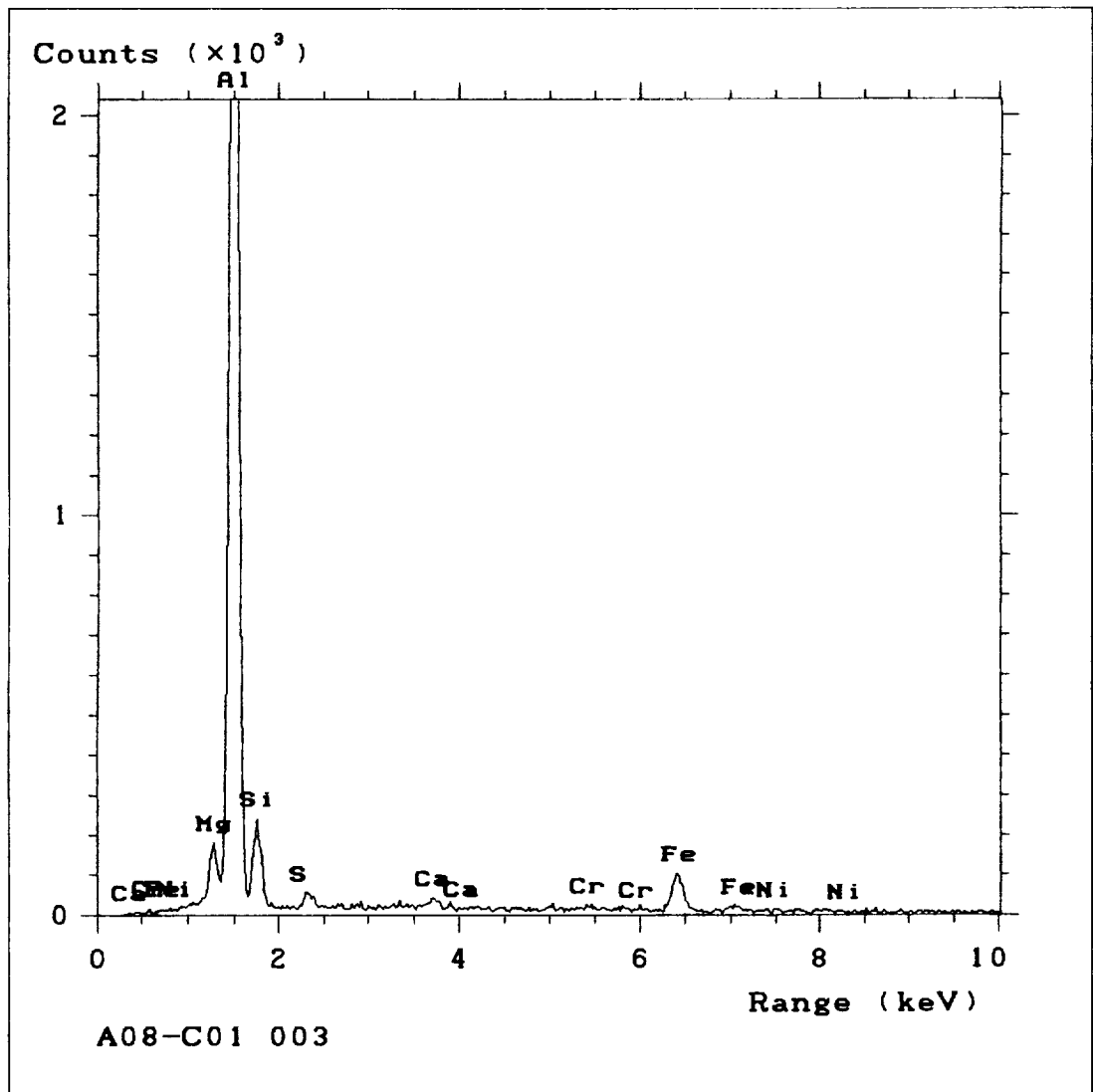
CLAMP NUMBER A08 CO1

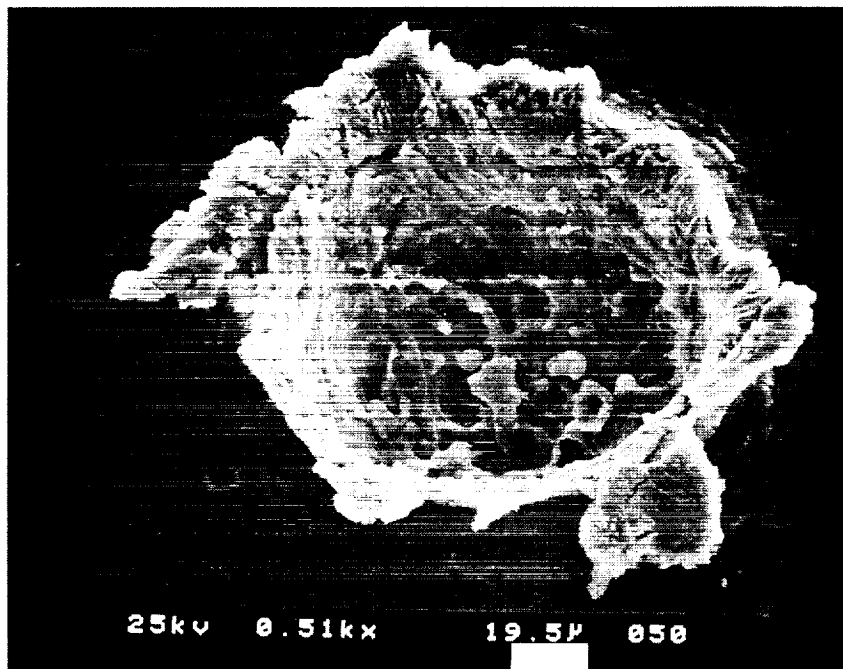
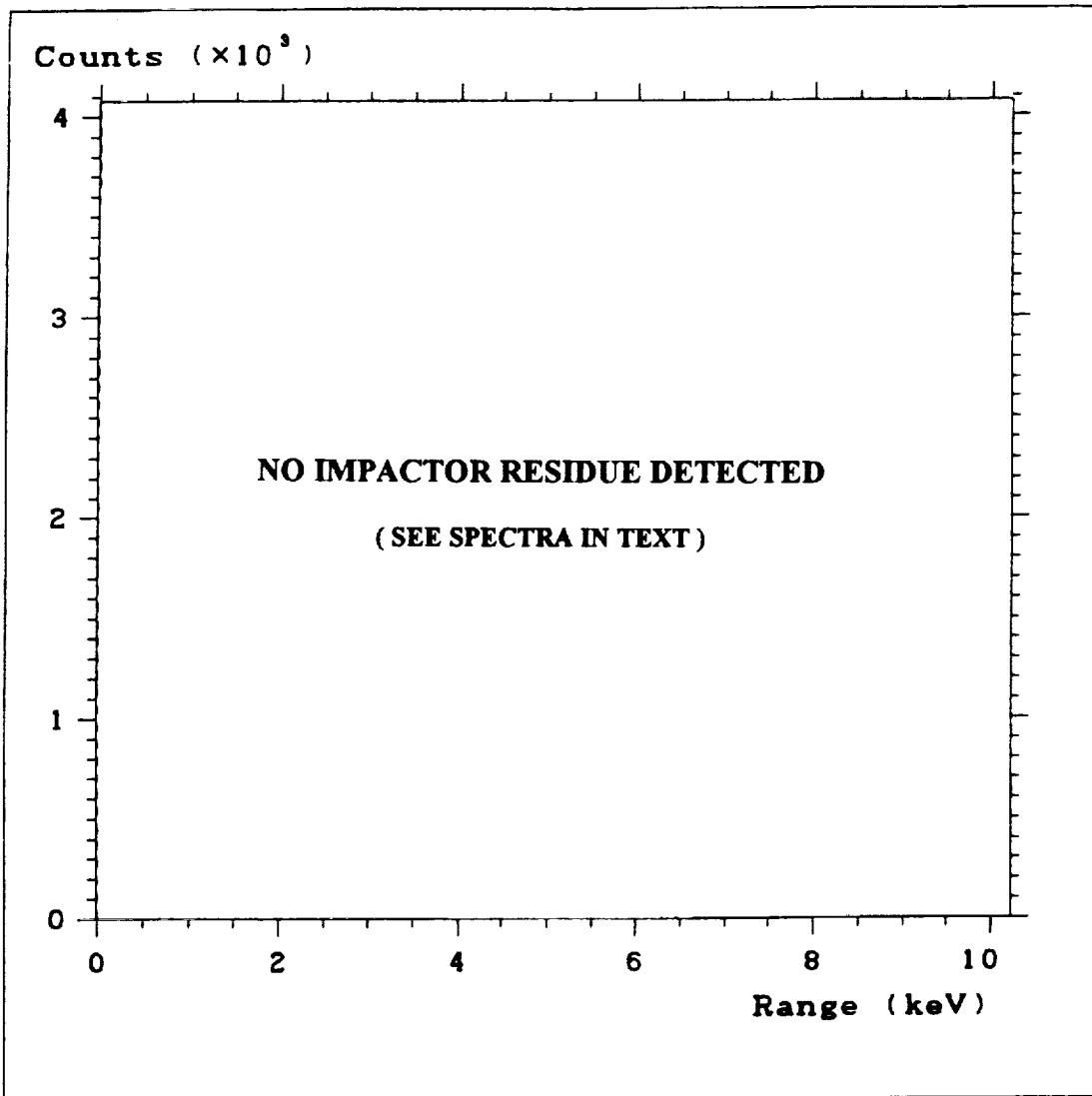
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	900	Si, Mg, Ca, Fe
002	130	Mg, Si, Ca, Fe
003	250	Trace
004	140	Unknown
005	200	Si, Mg, K
006	80	Si, Mg, Fe, Ca
007	100	Unkown
008	110	Unkown

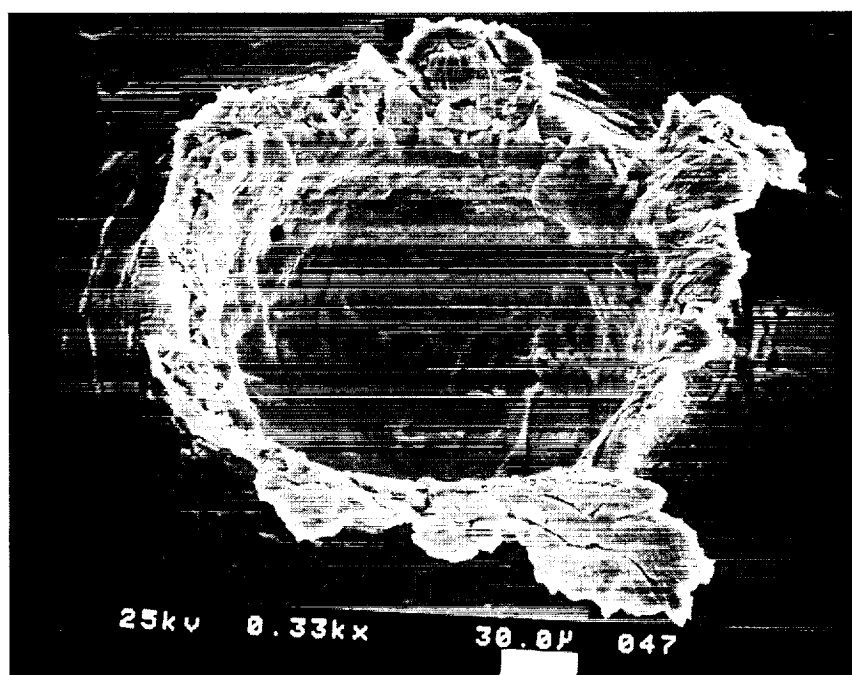
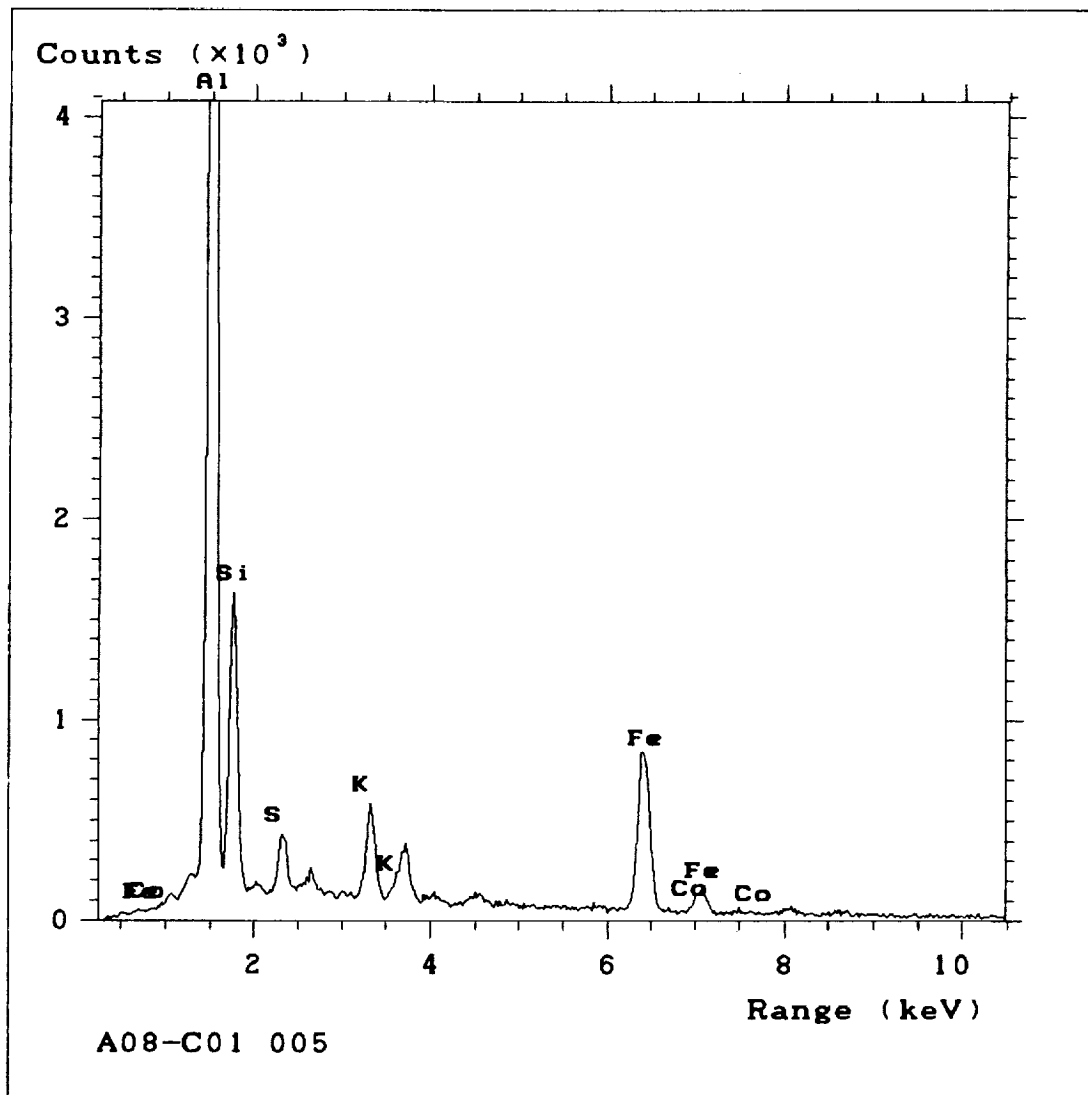


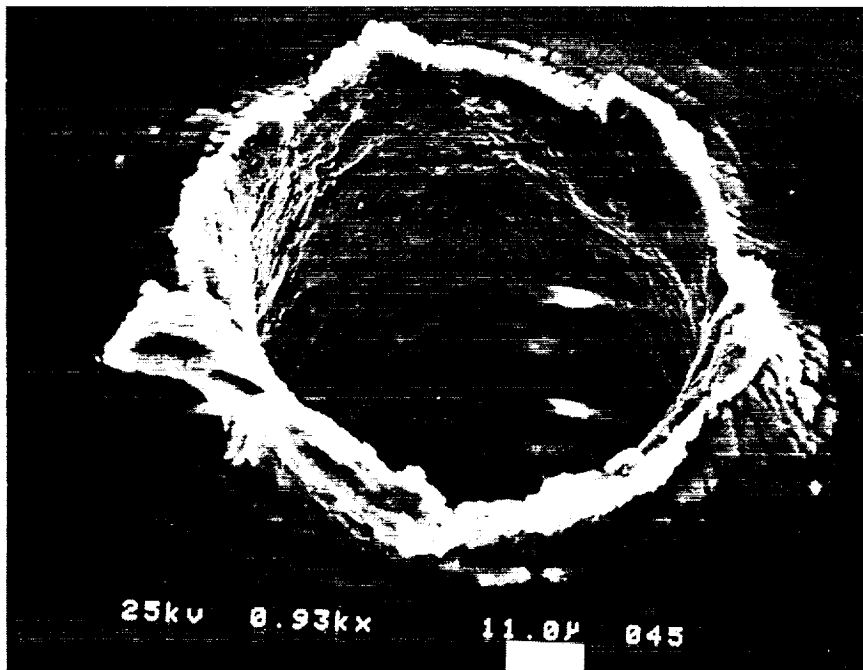
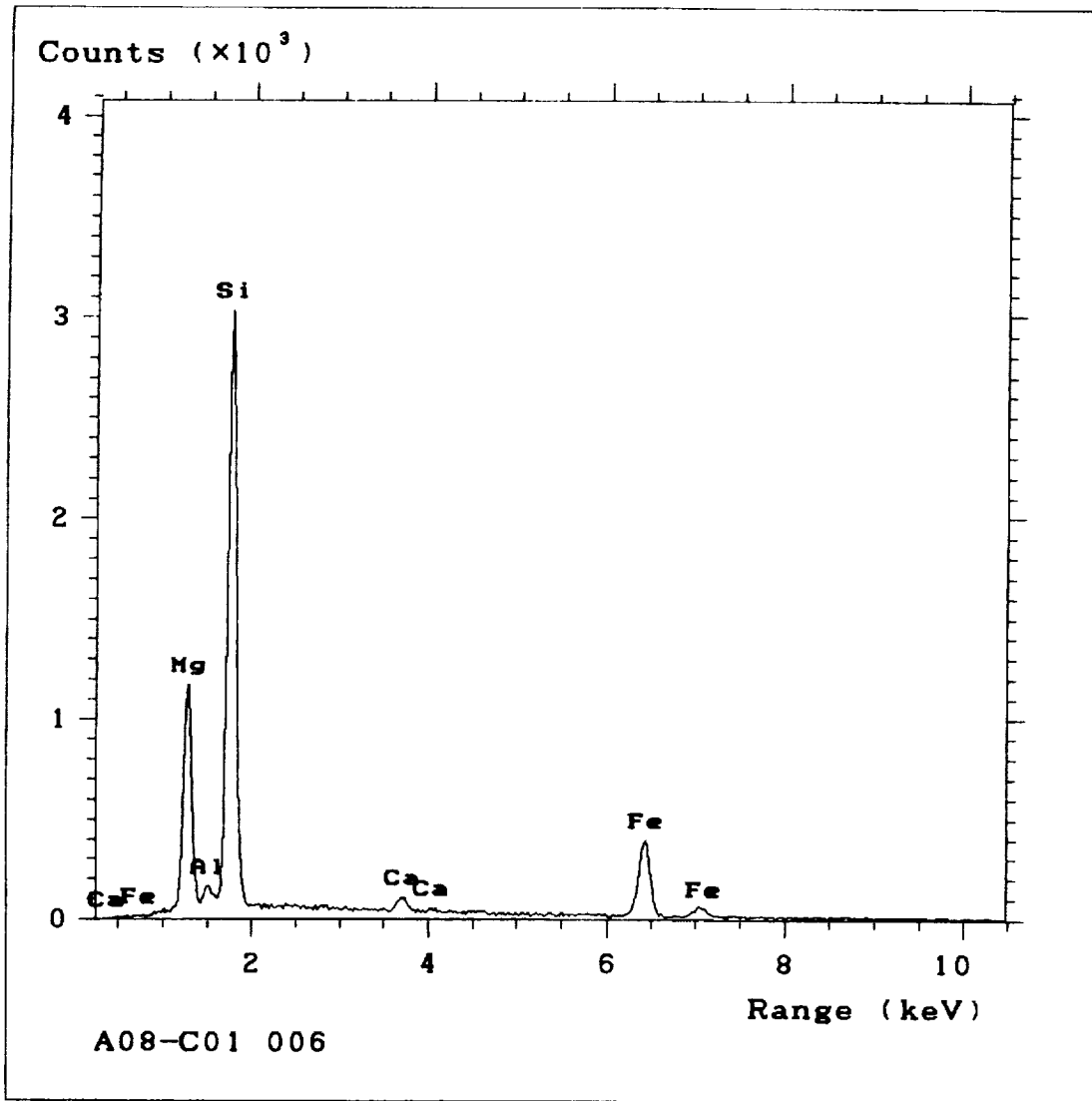


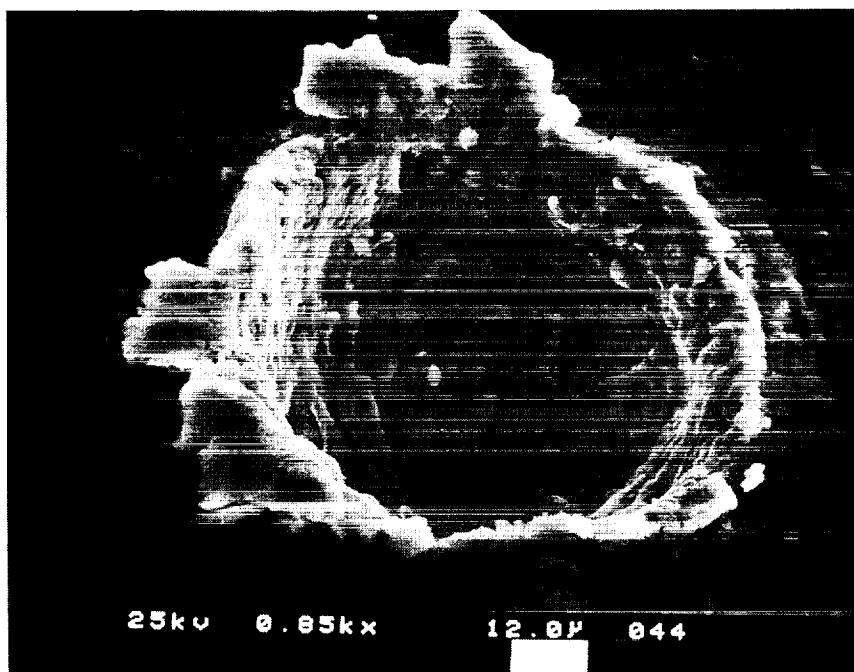
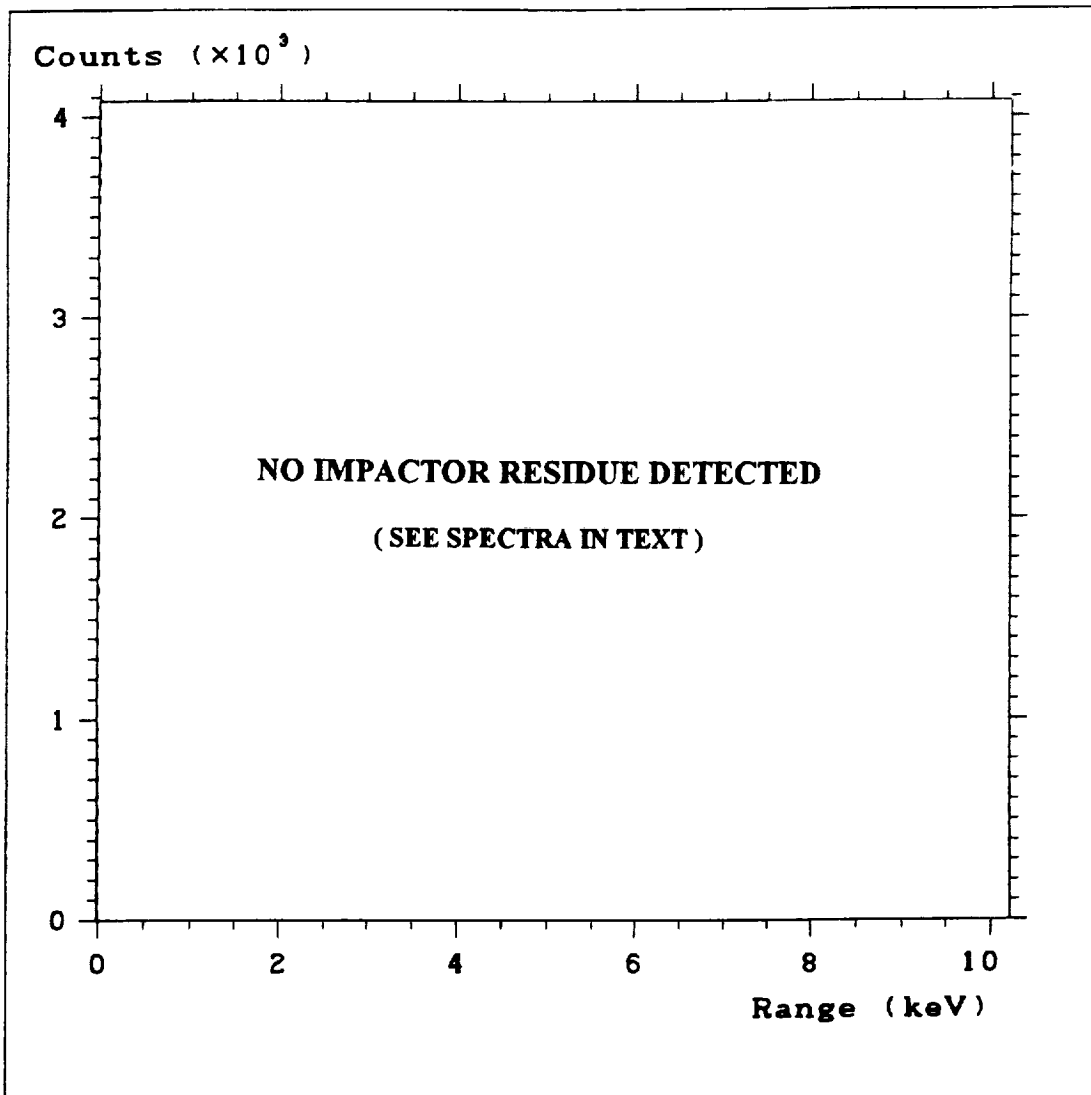


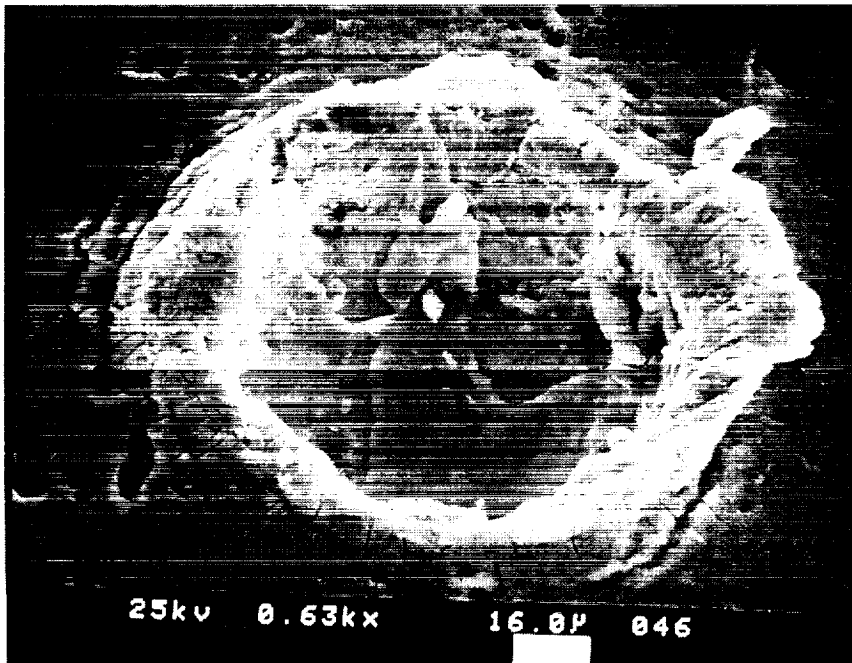
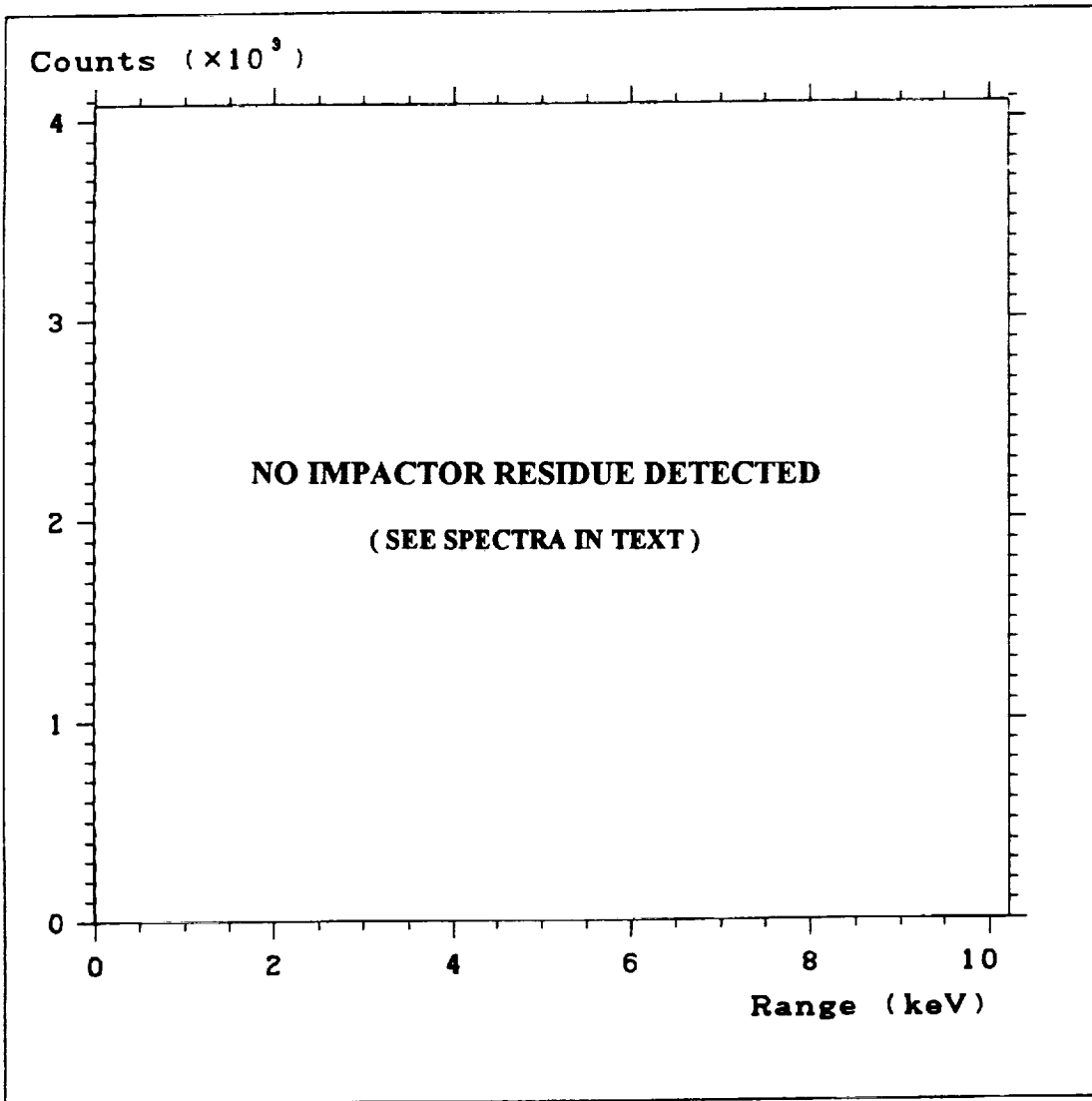






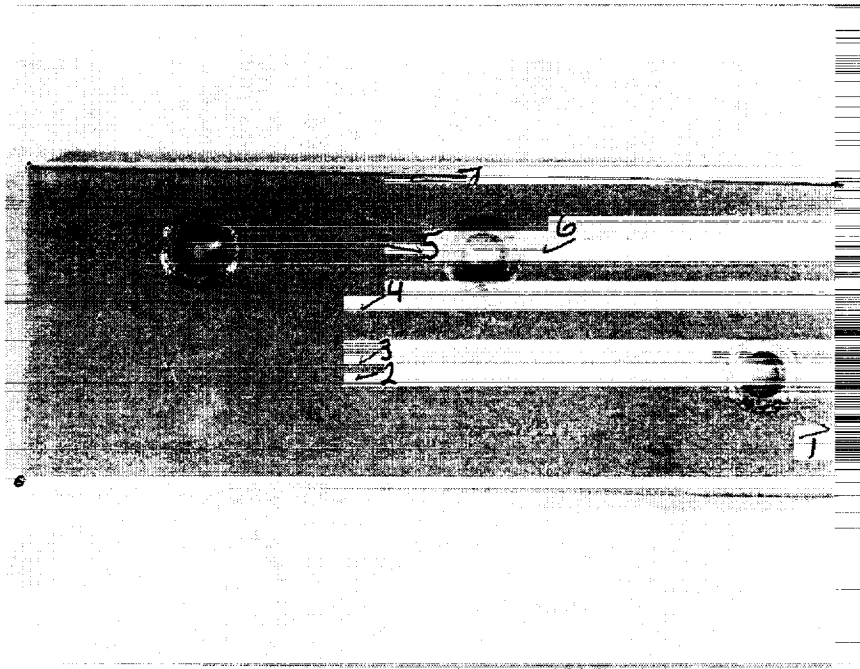


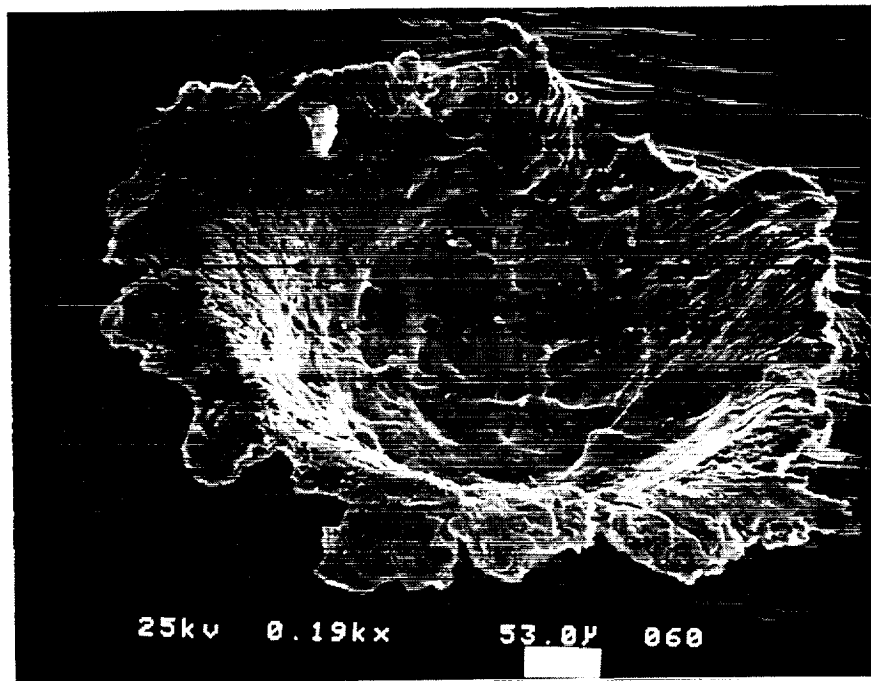
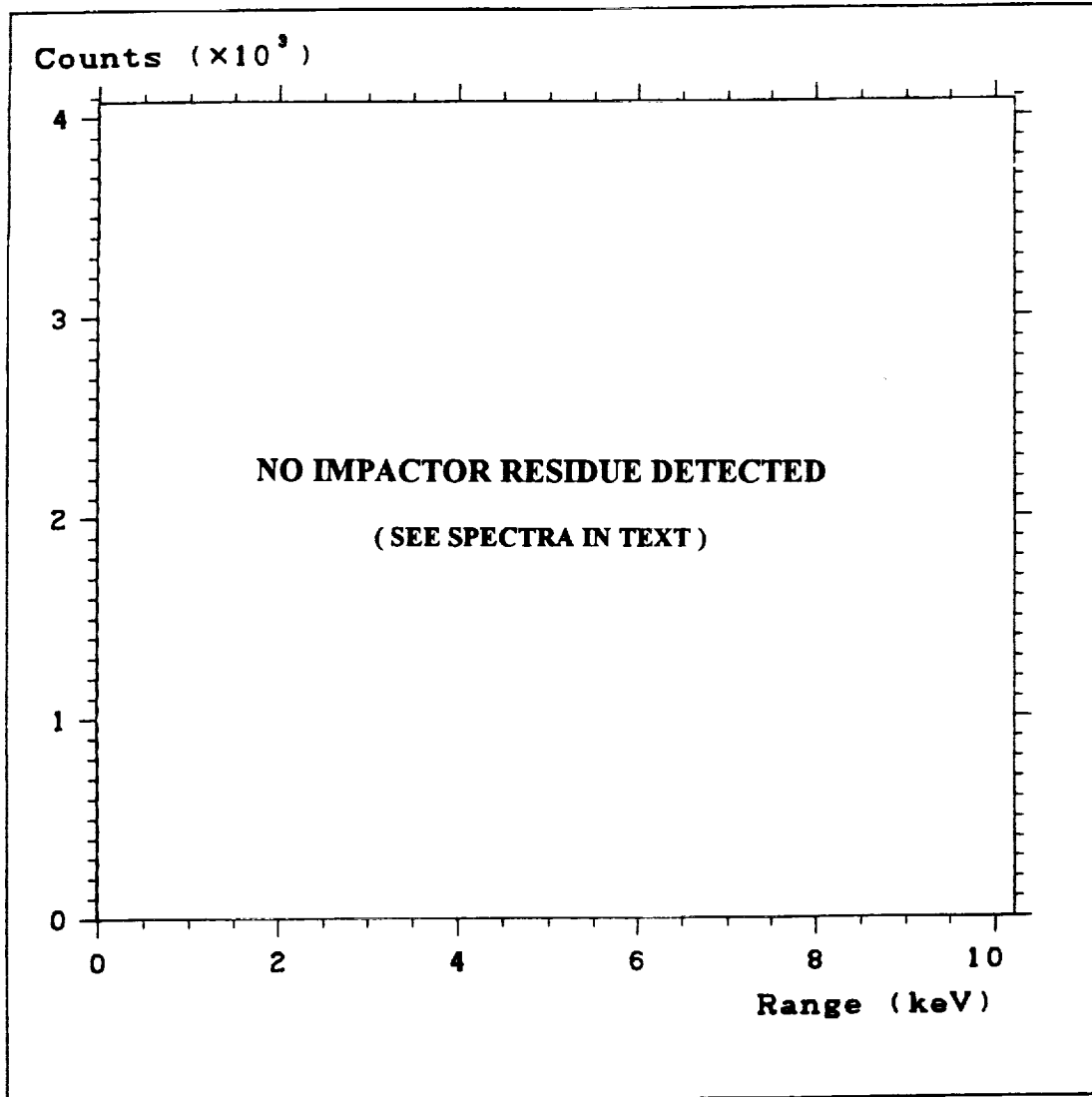


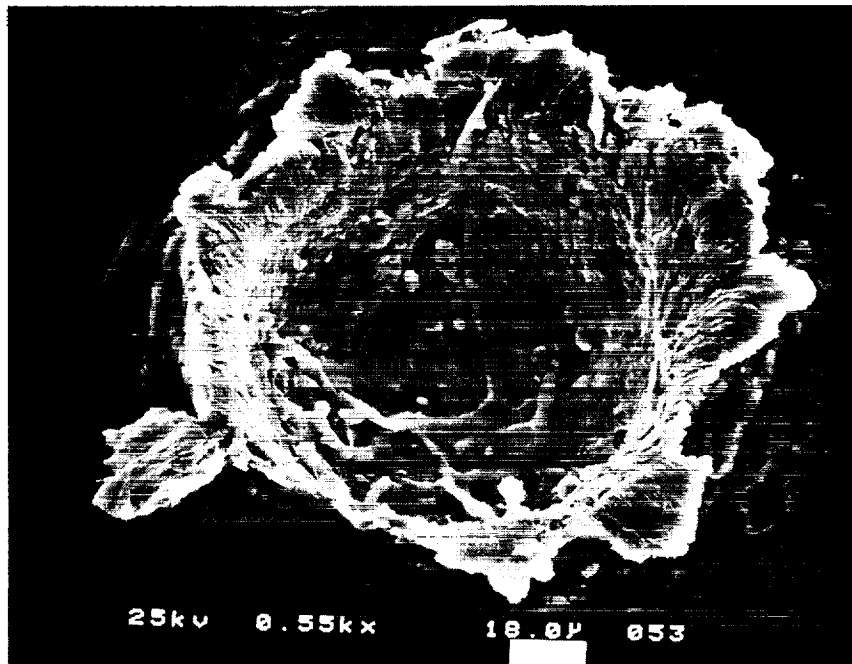
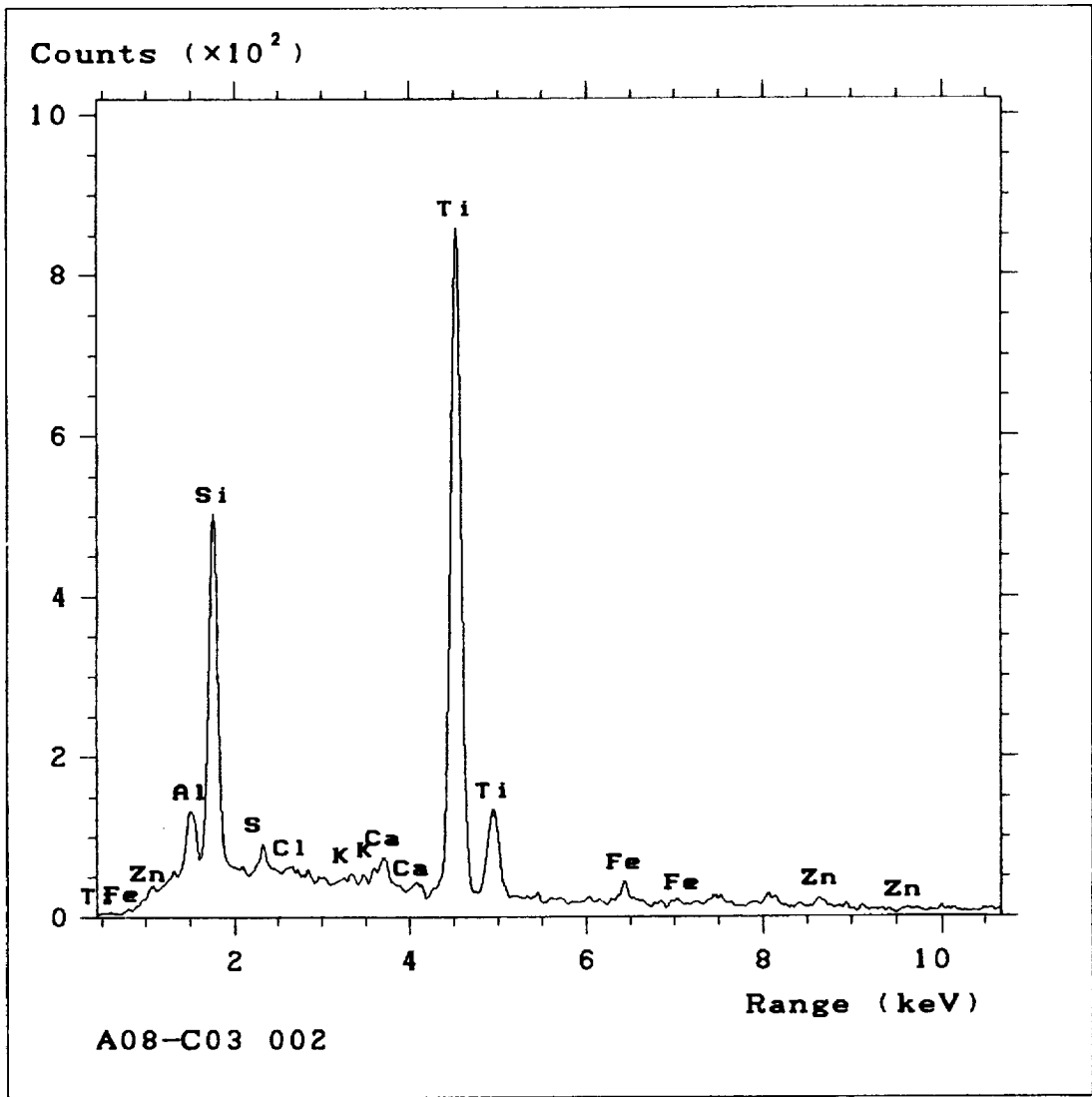


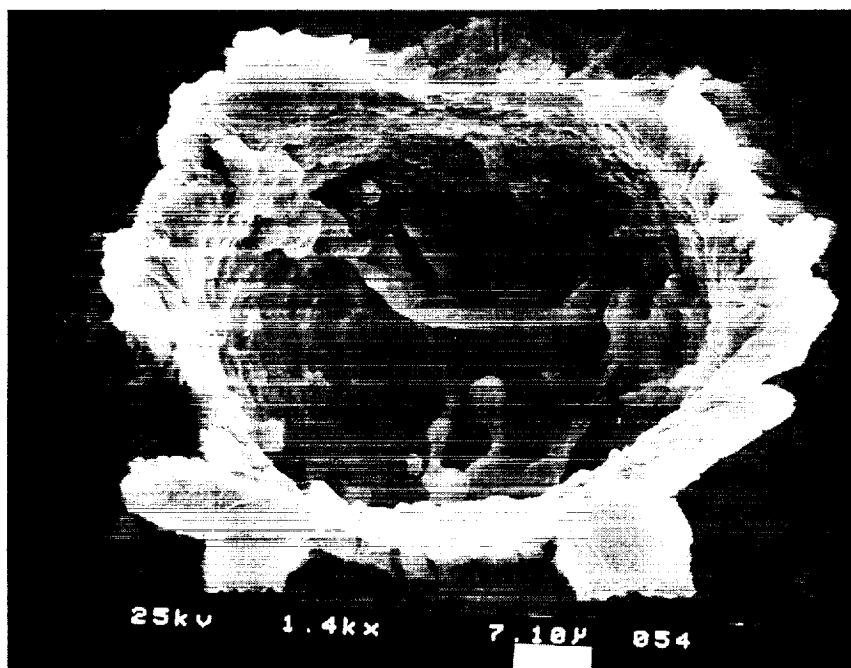
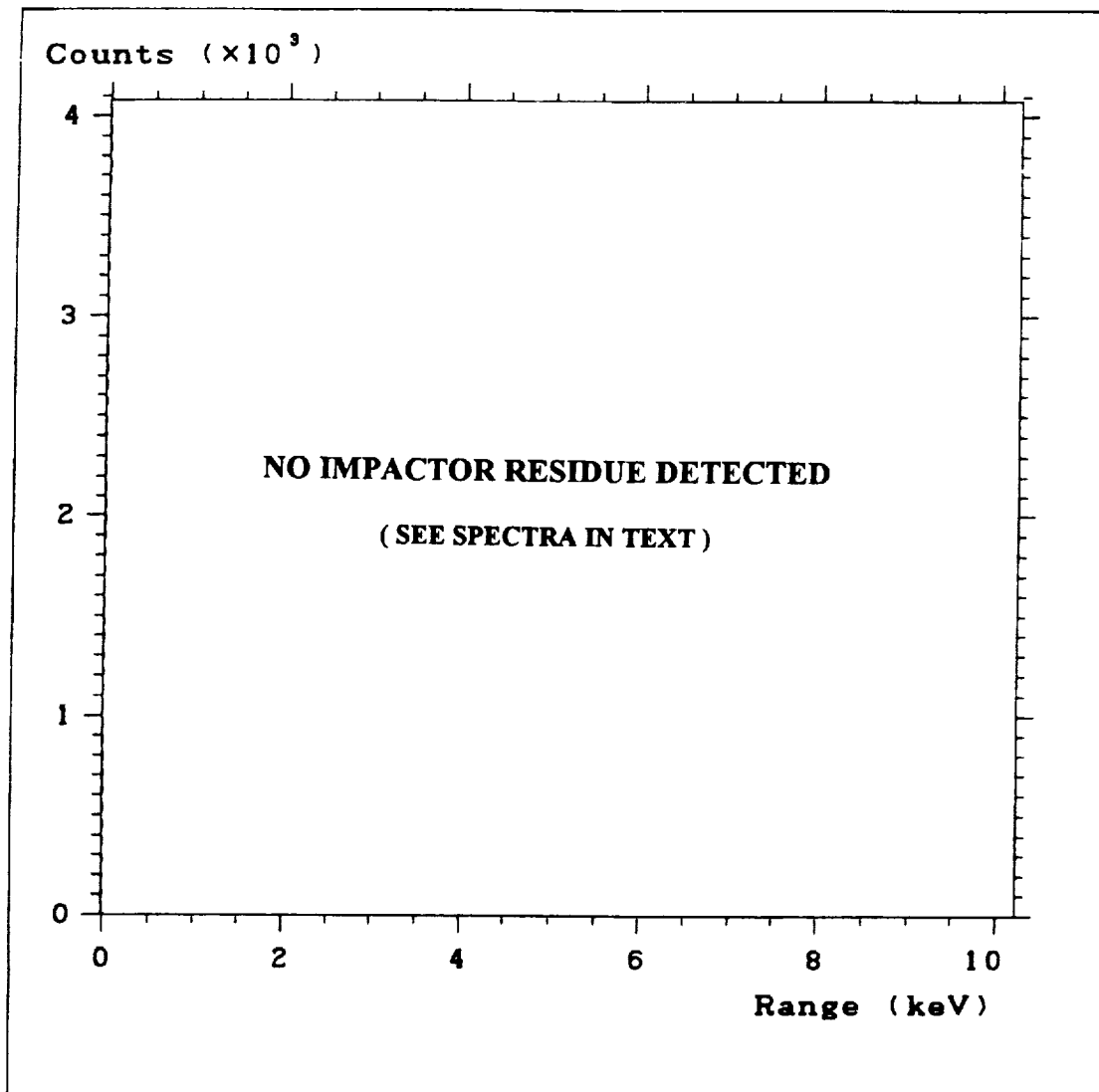
CLAMP NUMBER A08 CO3

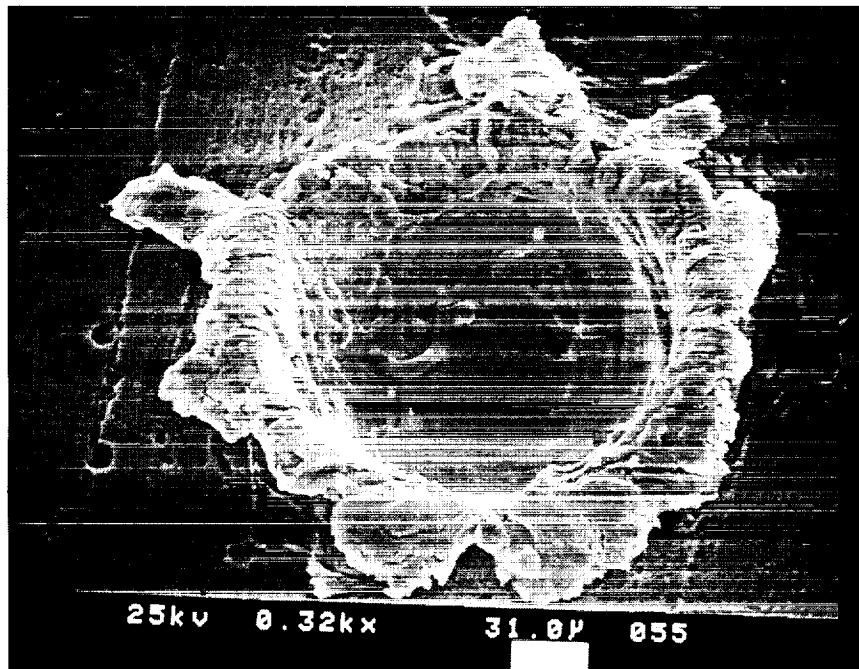
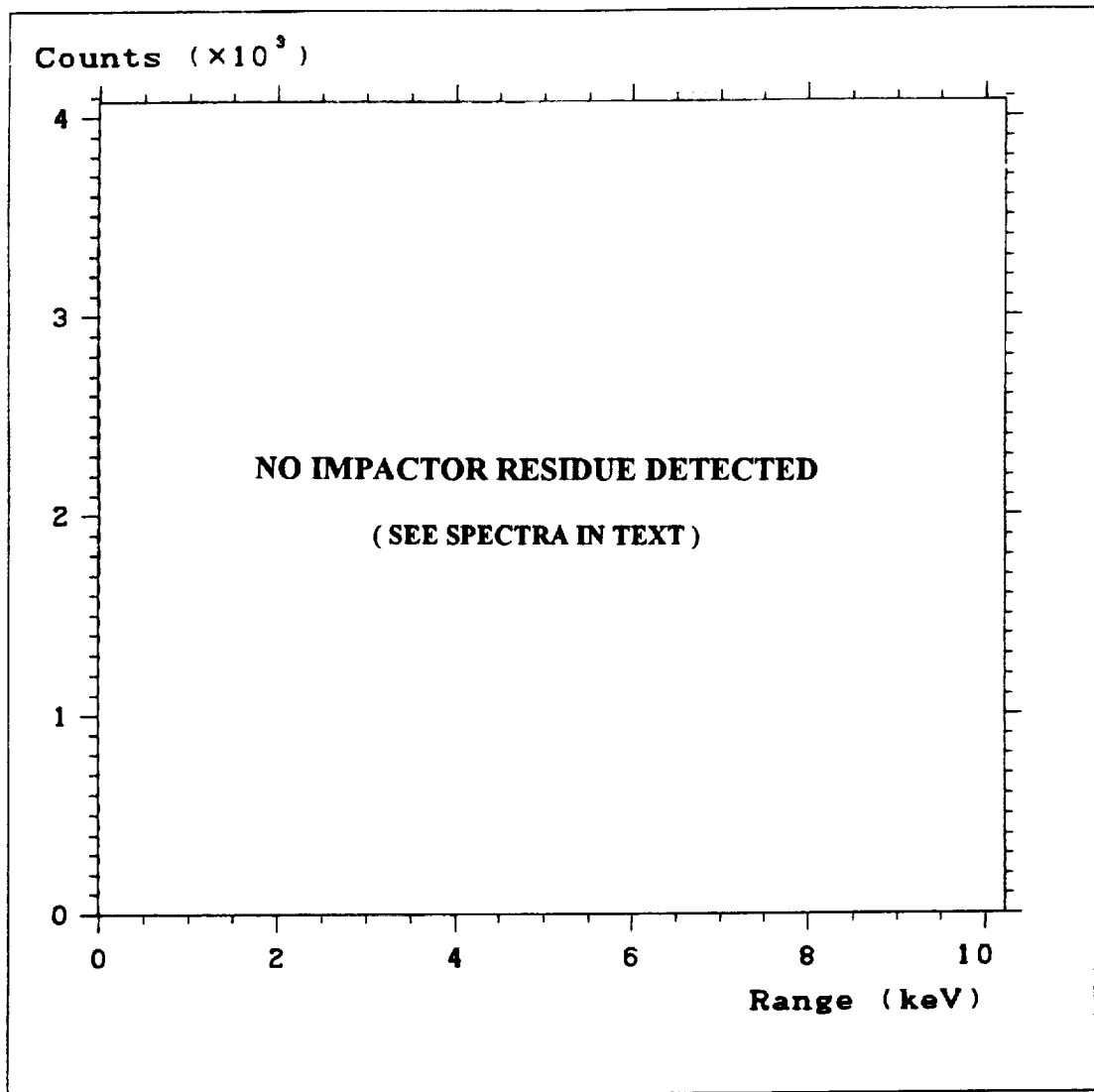
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	400	Unkown
002	140	Paint
003	80	Unkown
004	200	Unkown
005	160	Unkown
006	150	Unkown
007	380	Unkown

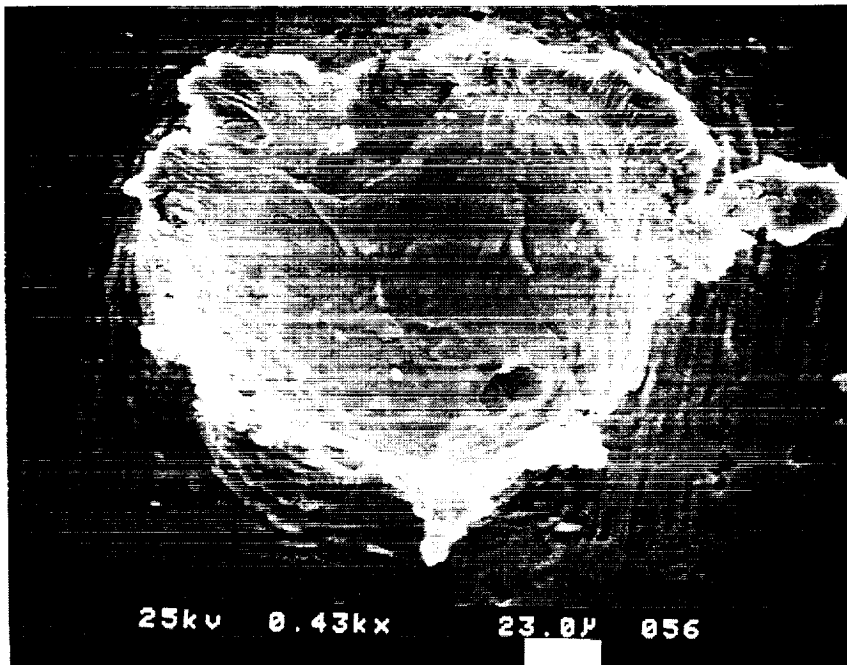
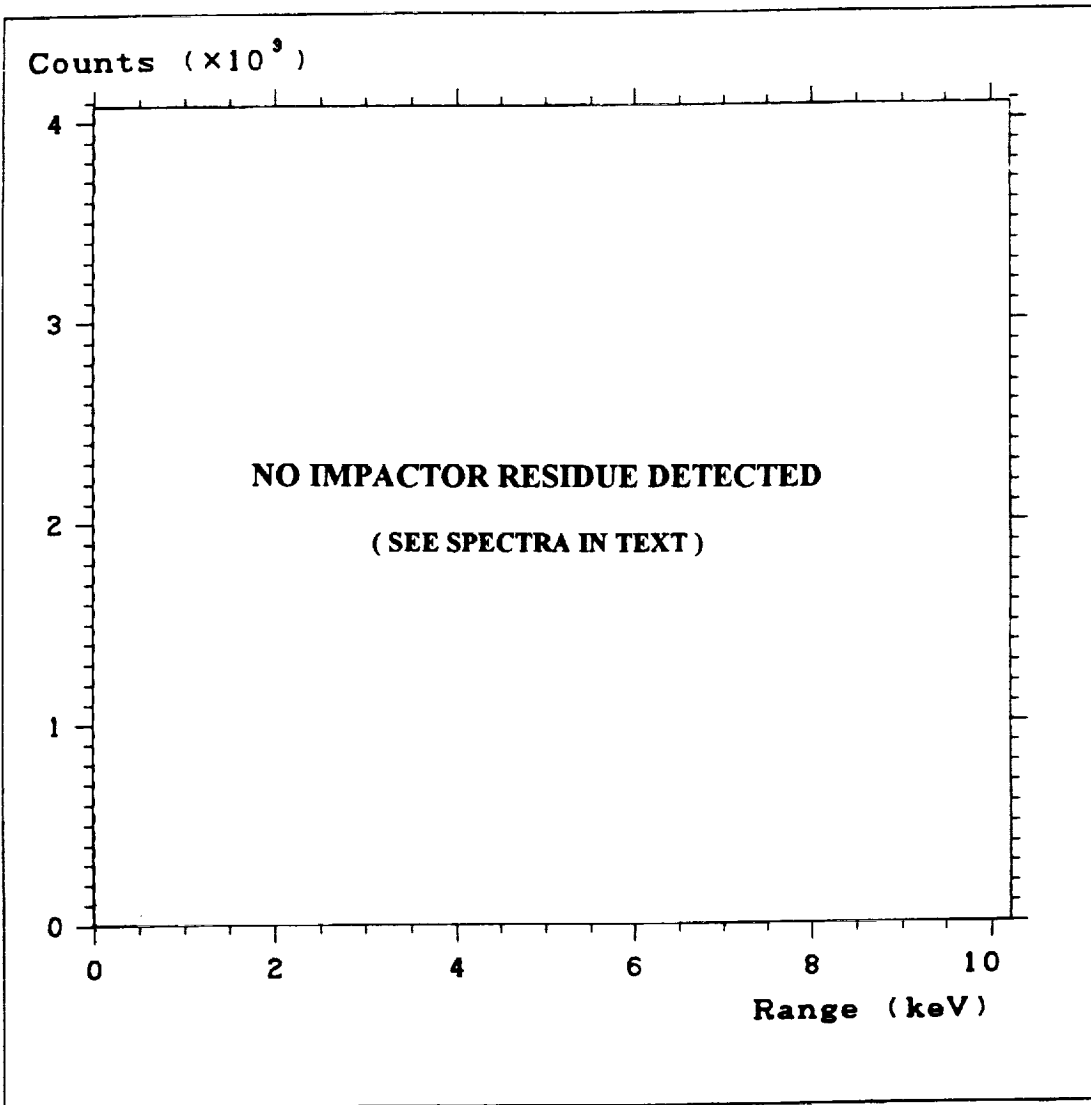


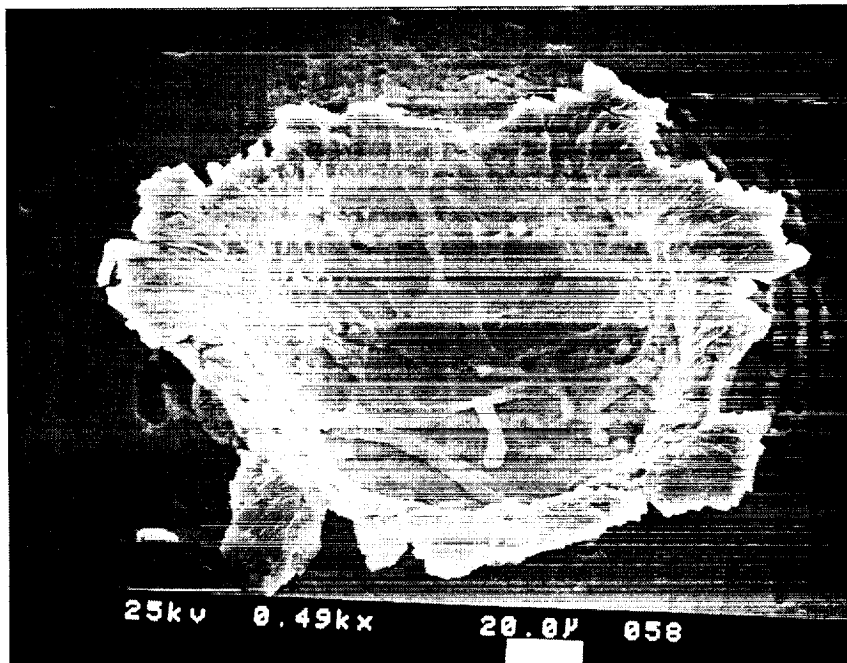
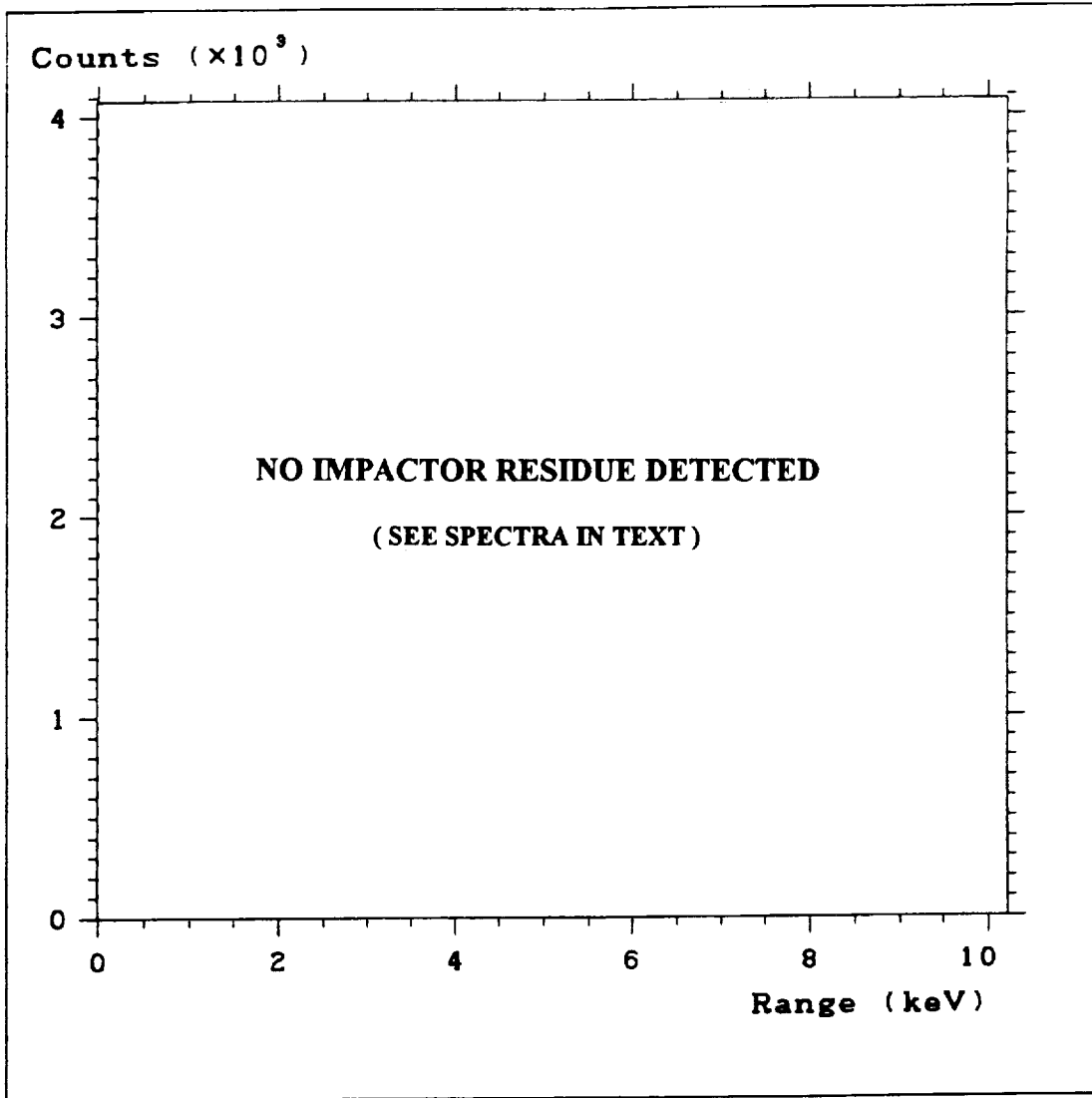


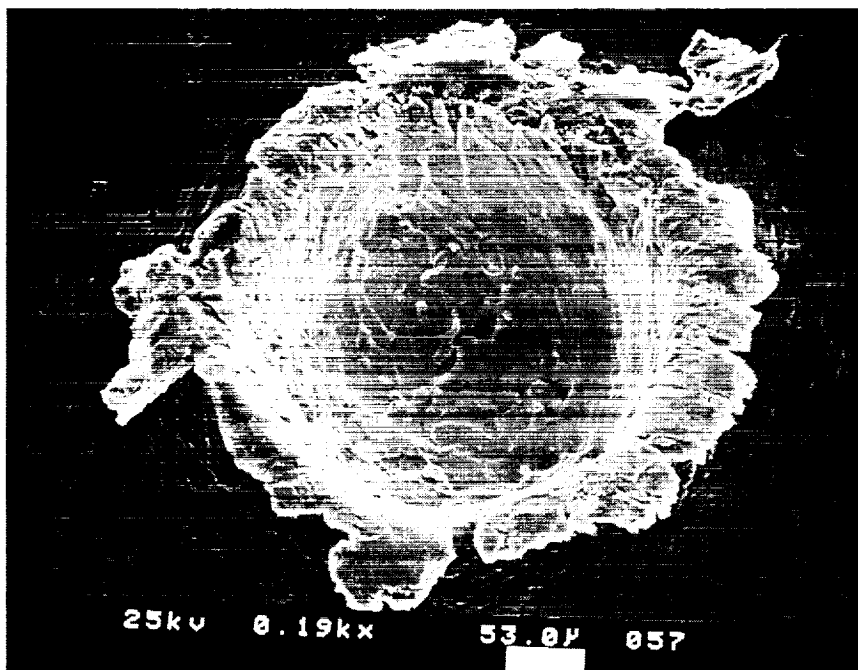
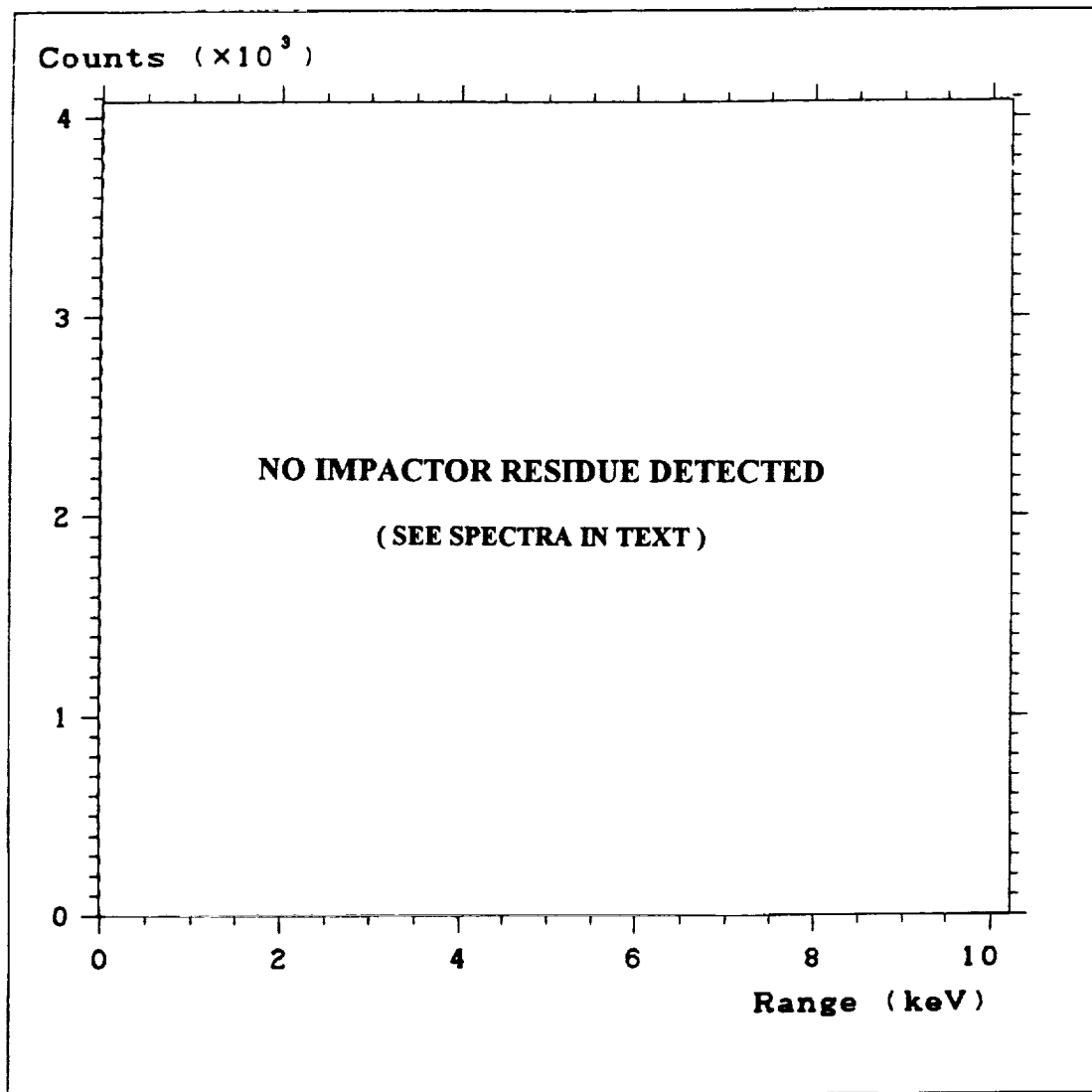






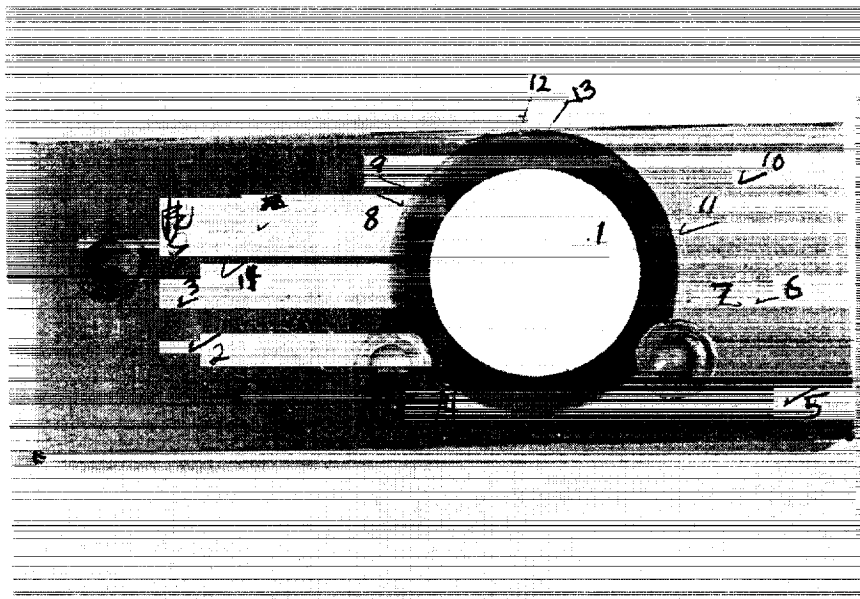


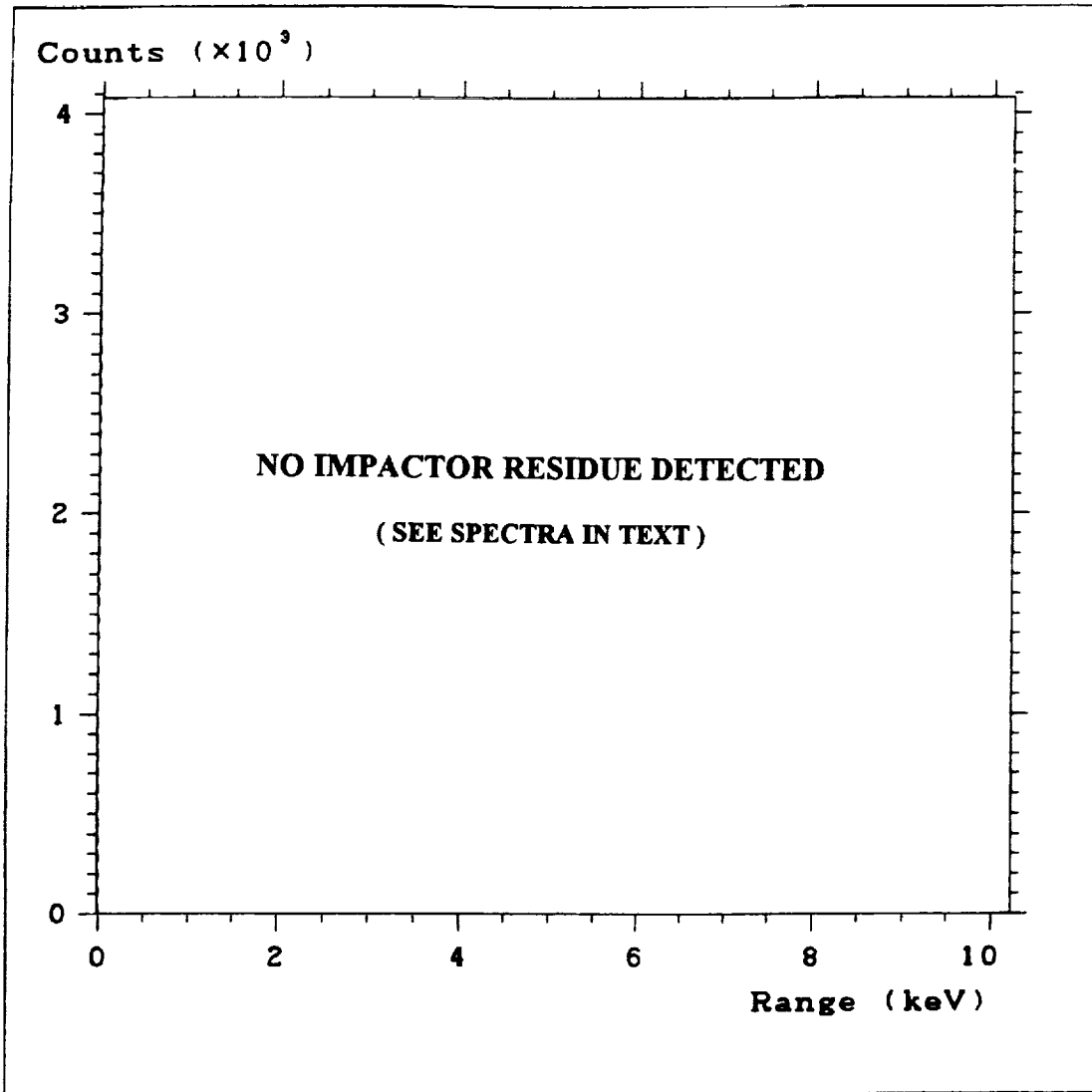


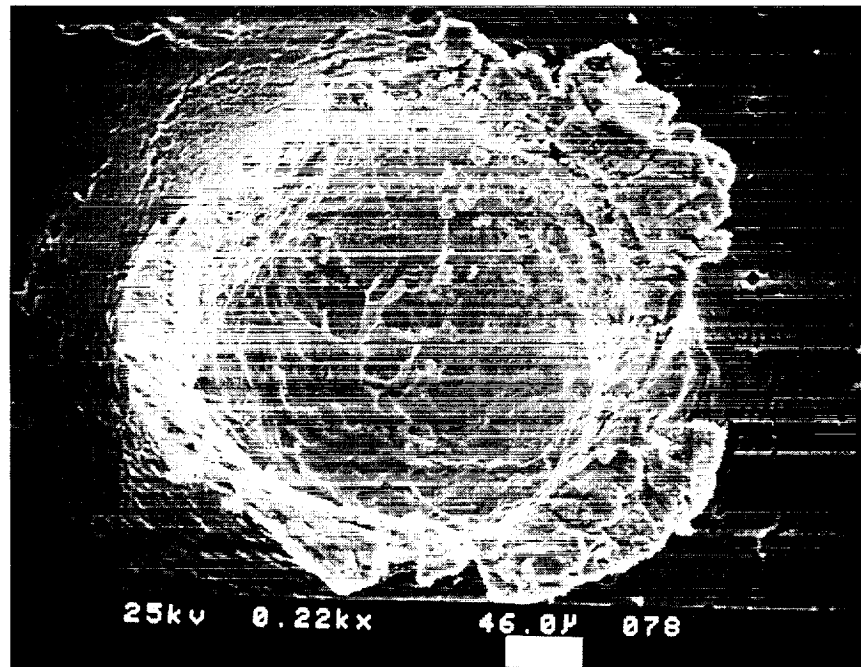
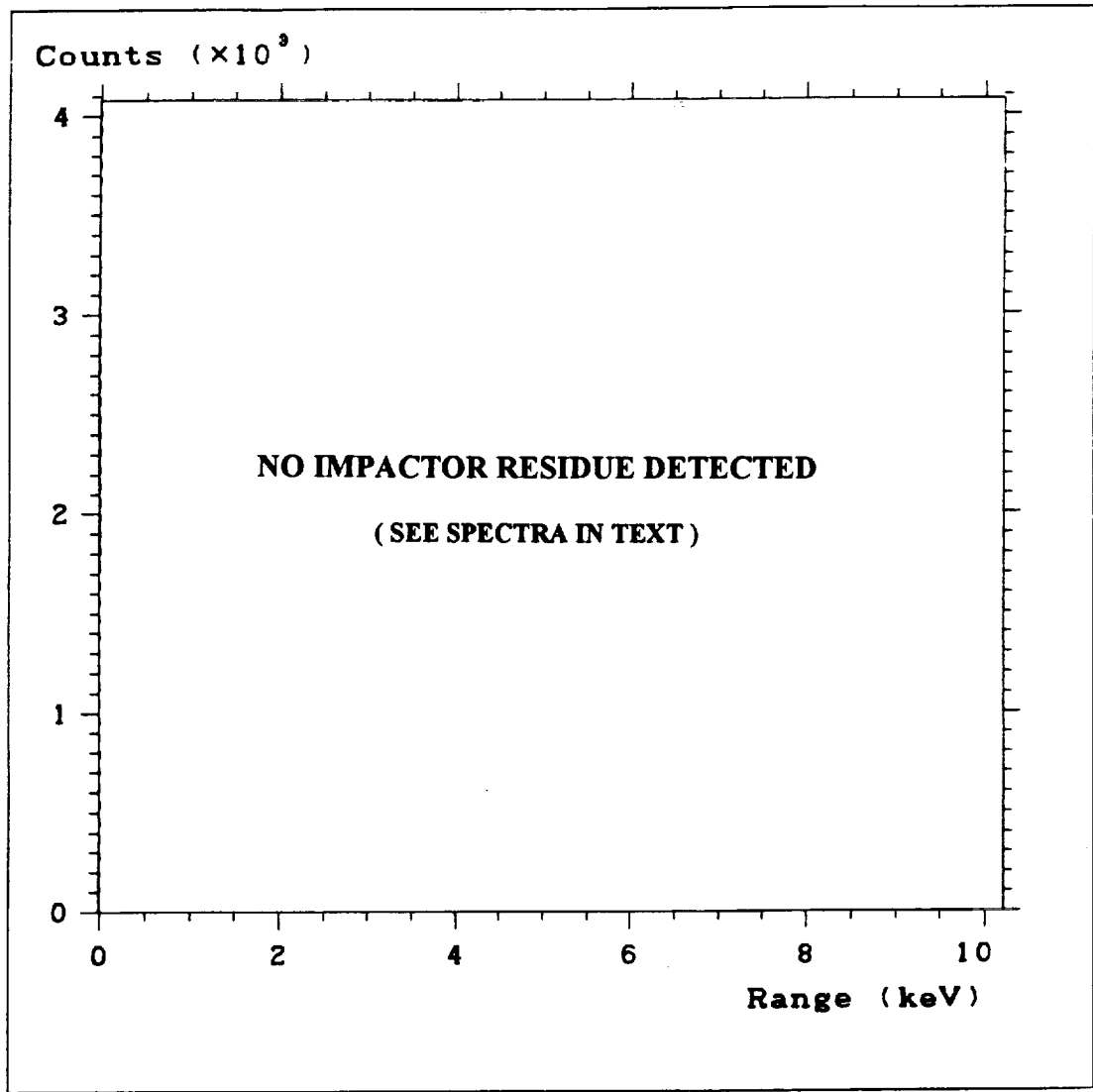


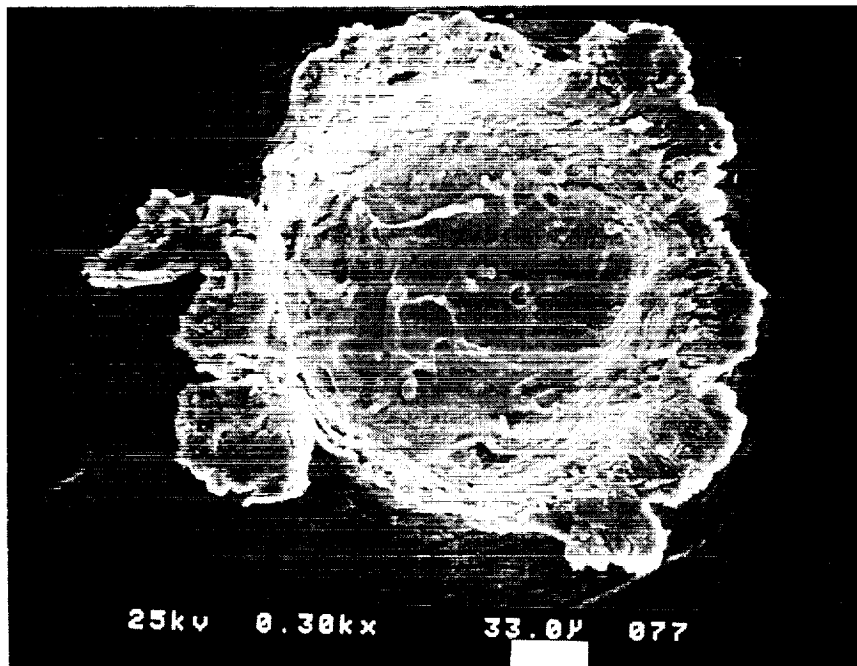
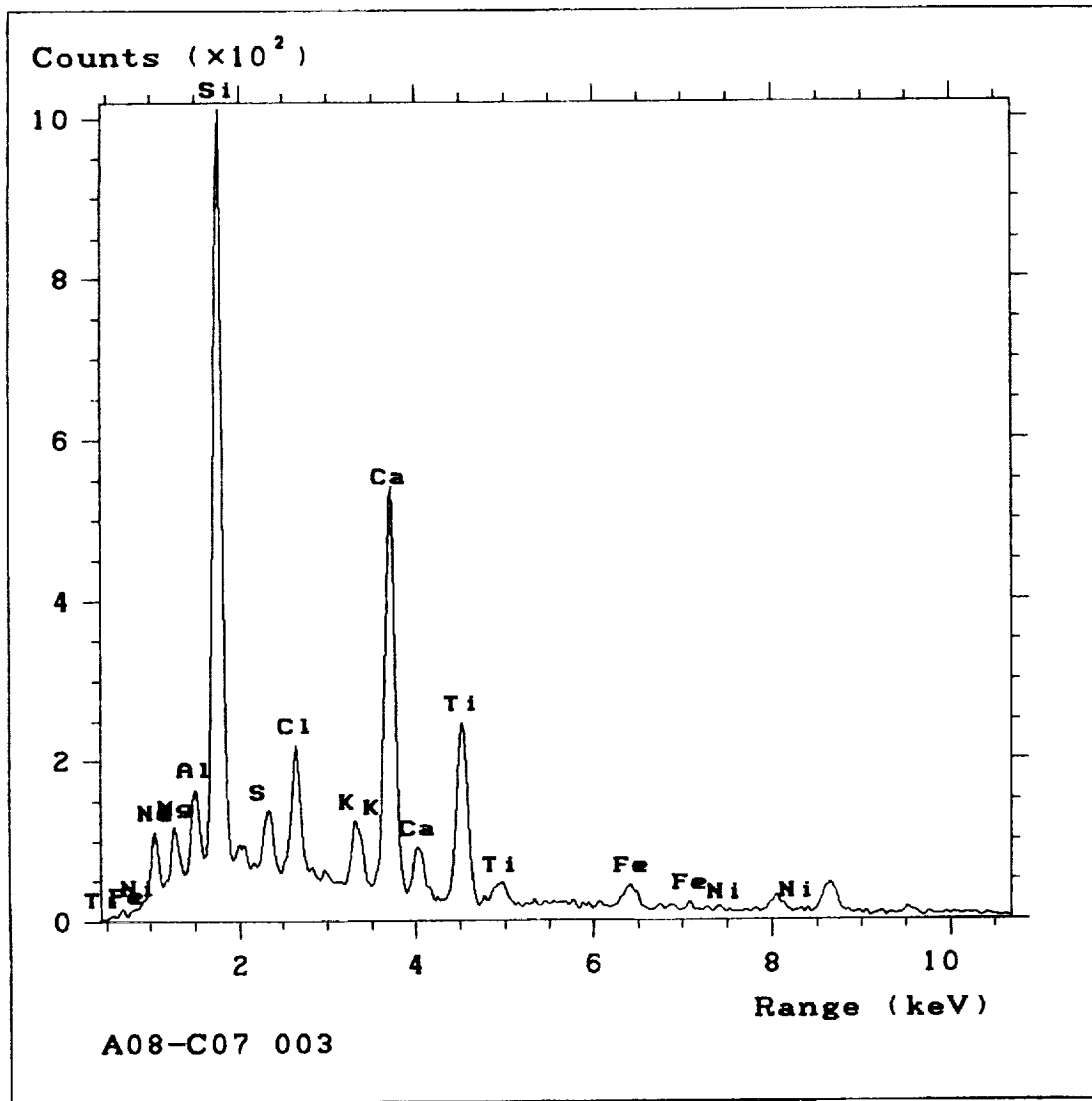
CLAMP NUMBER A08 CO7

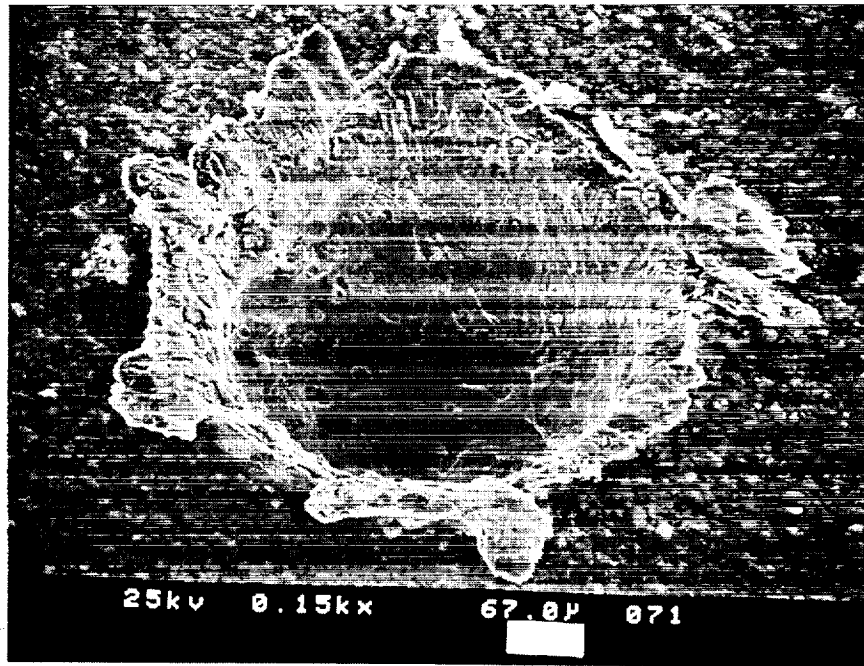
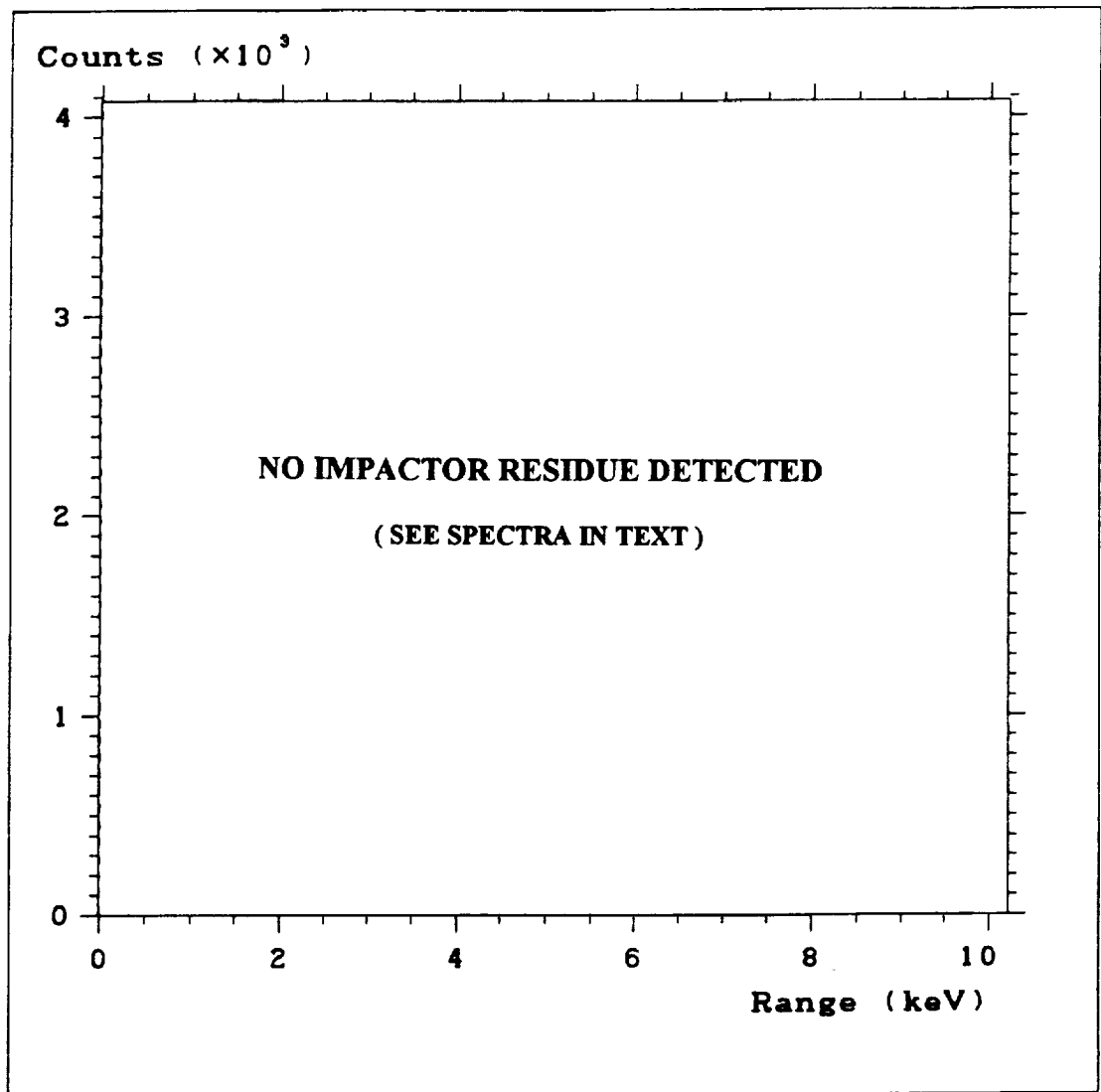
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	360	Paint Patch
002	350	Unkown
003	270	Paint
004	470	Unkown
005	130	Si, Mg, Ca, Fe
006	60	Unkown
007	160	Contamination
008	60	Paint Patch
009	130	Unkown
010	170	Unkown
011	140	Paint Patch
012	230	Paint Patch
013	40	Paint Patch
014	100	Unkown

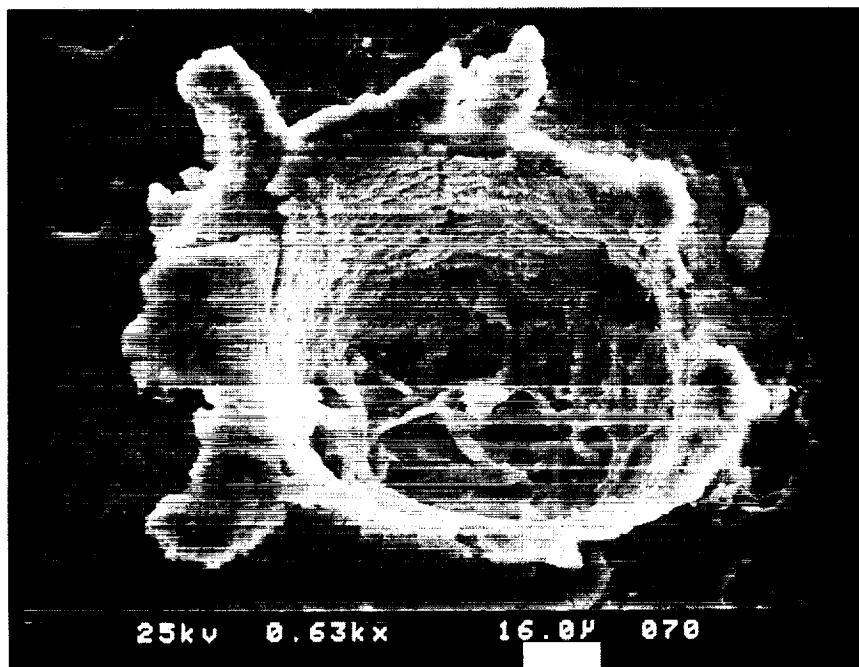
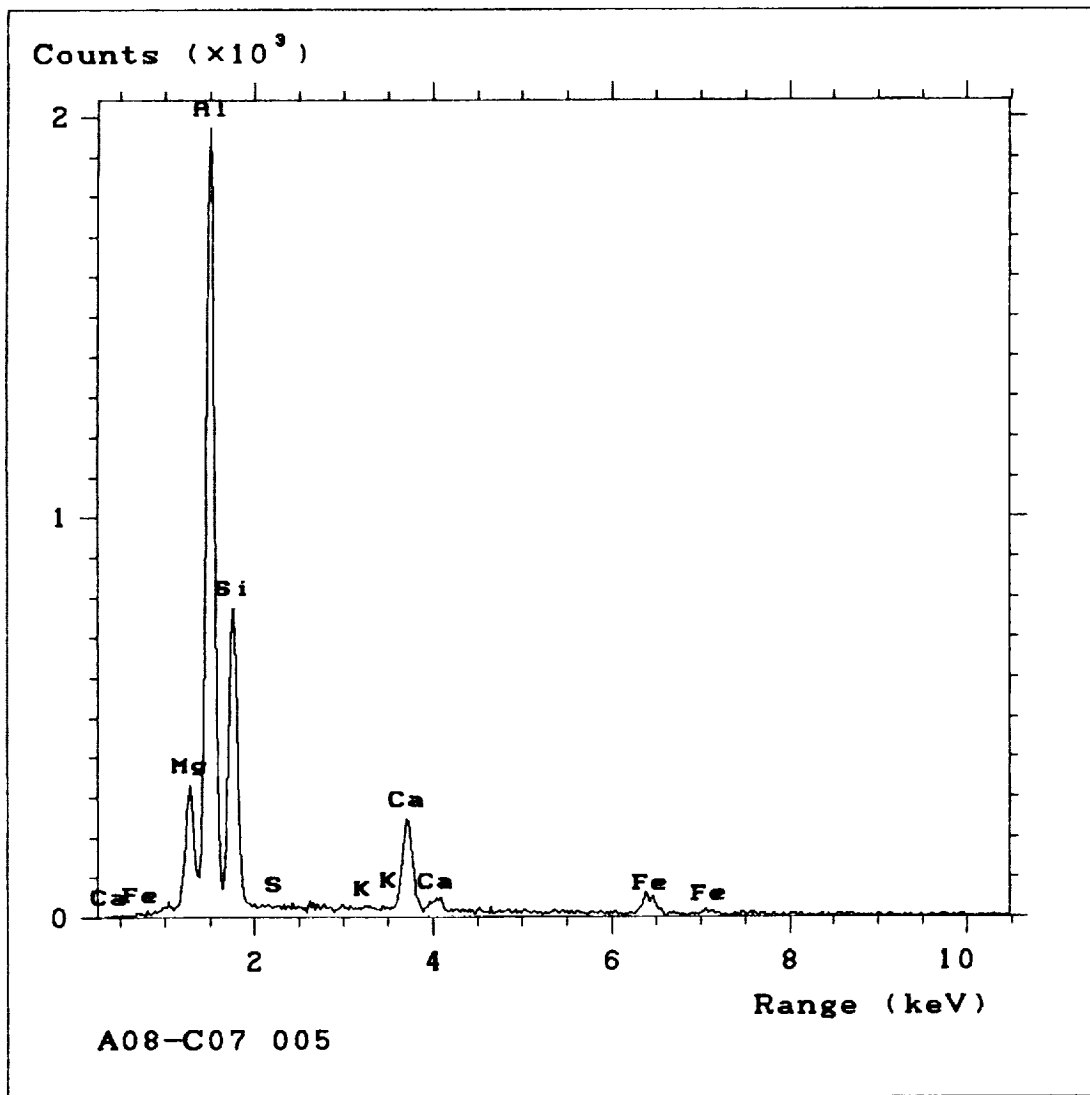


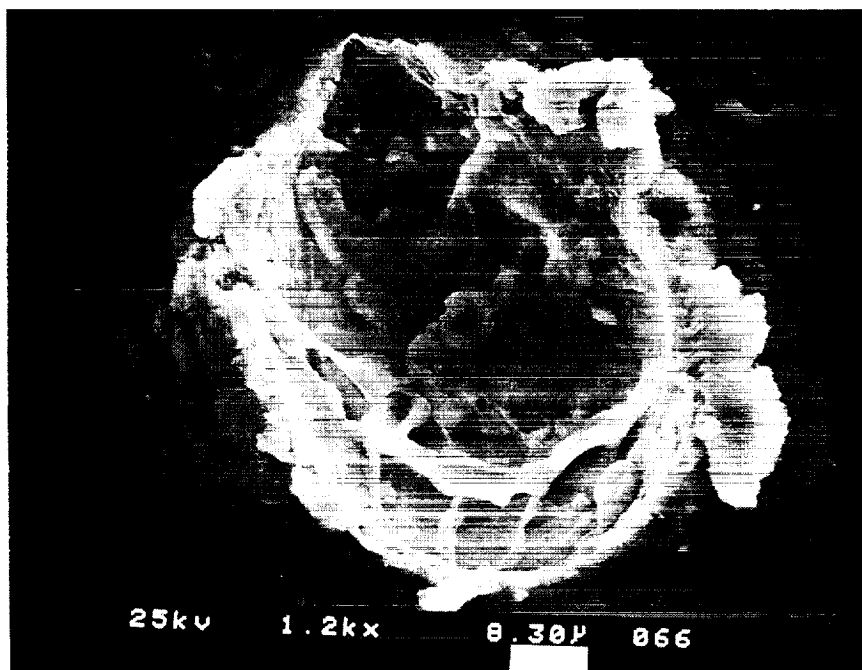
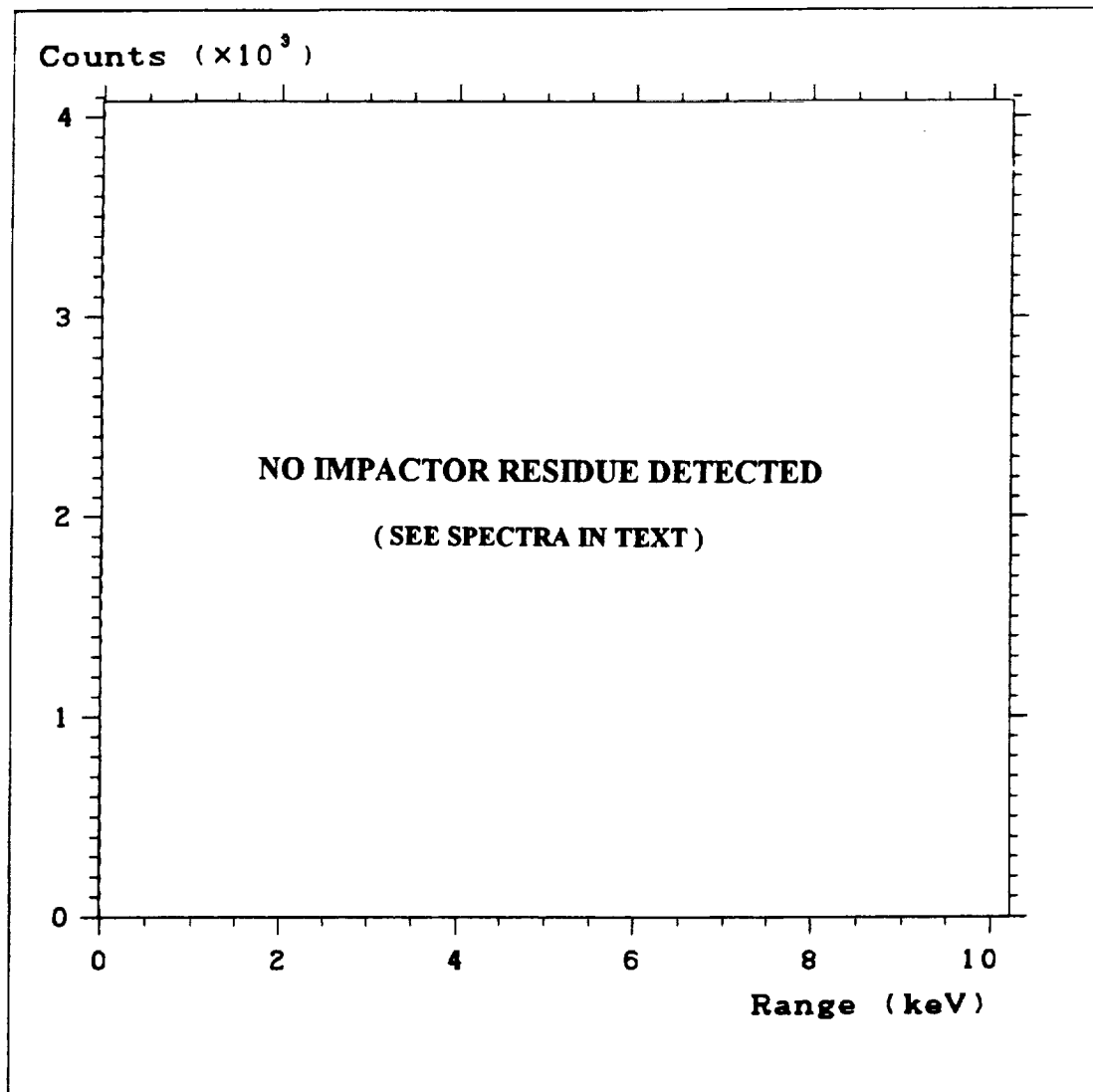


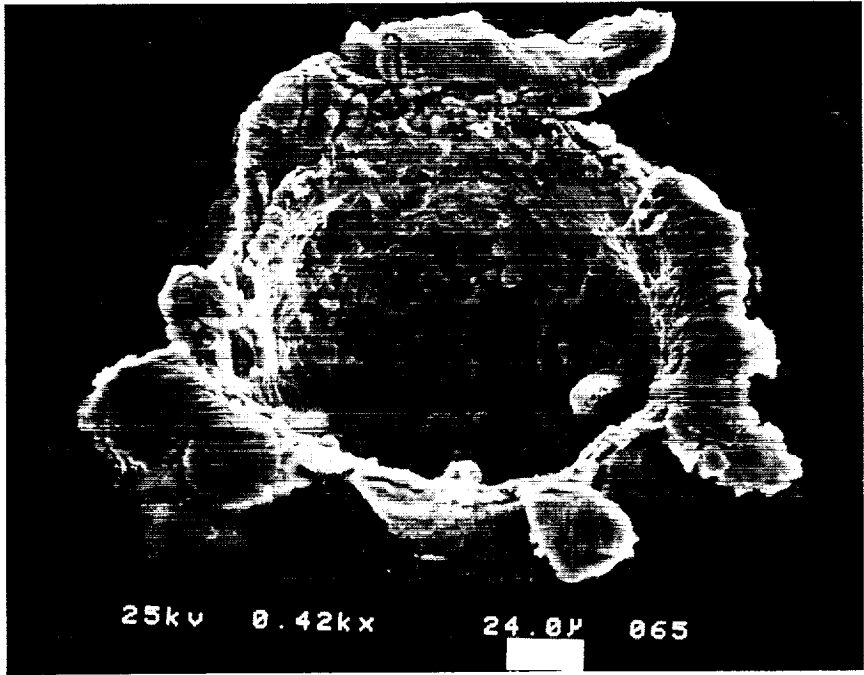
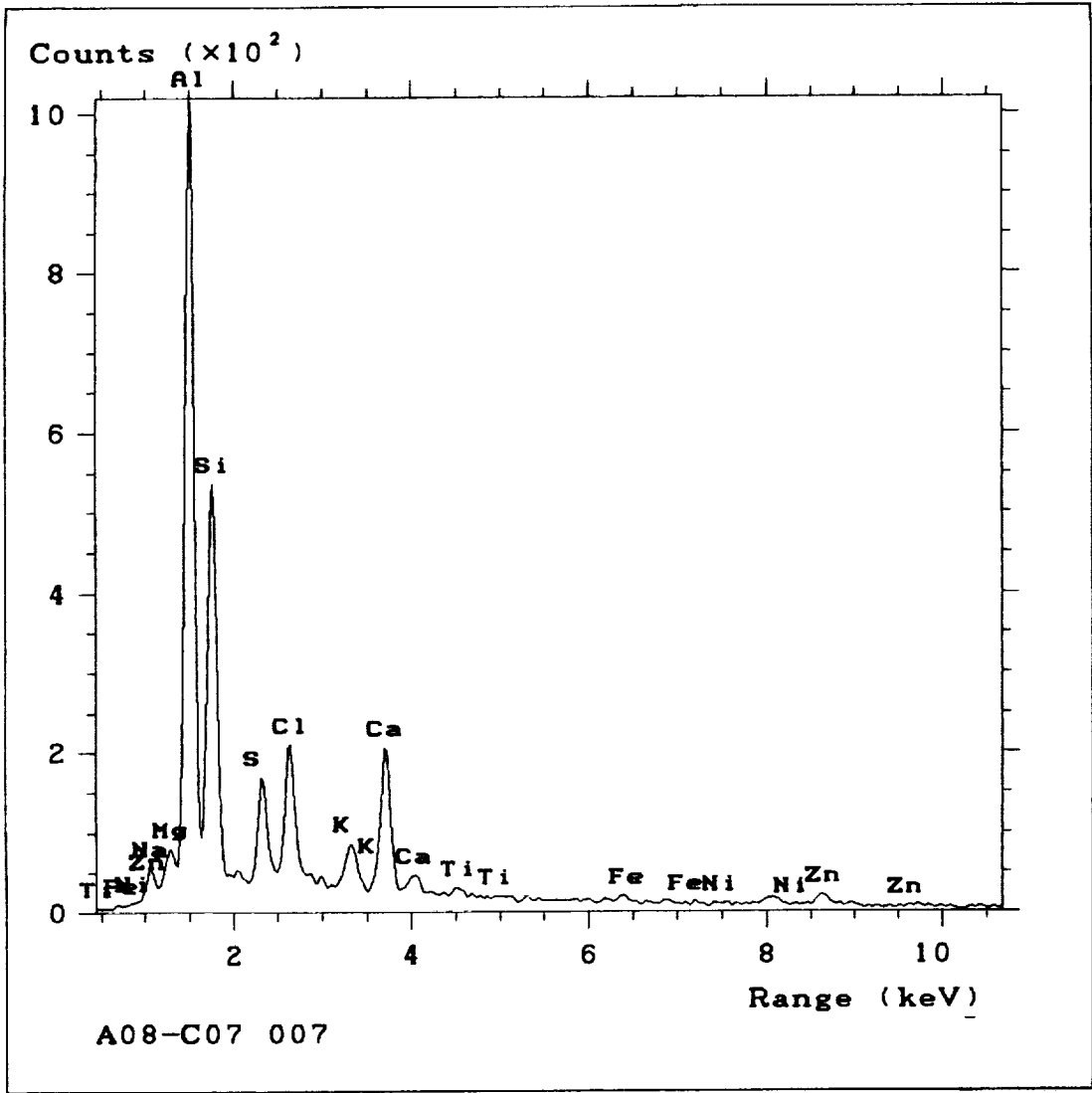


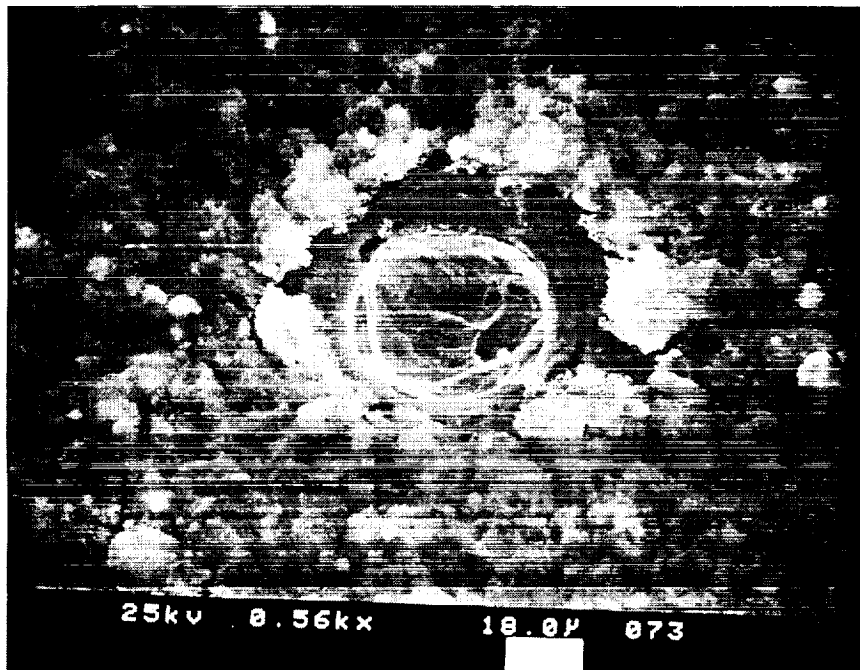
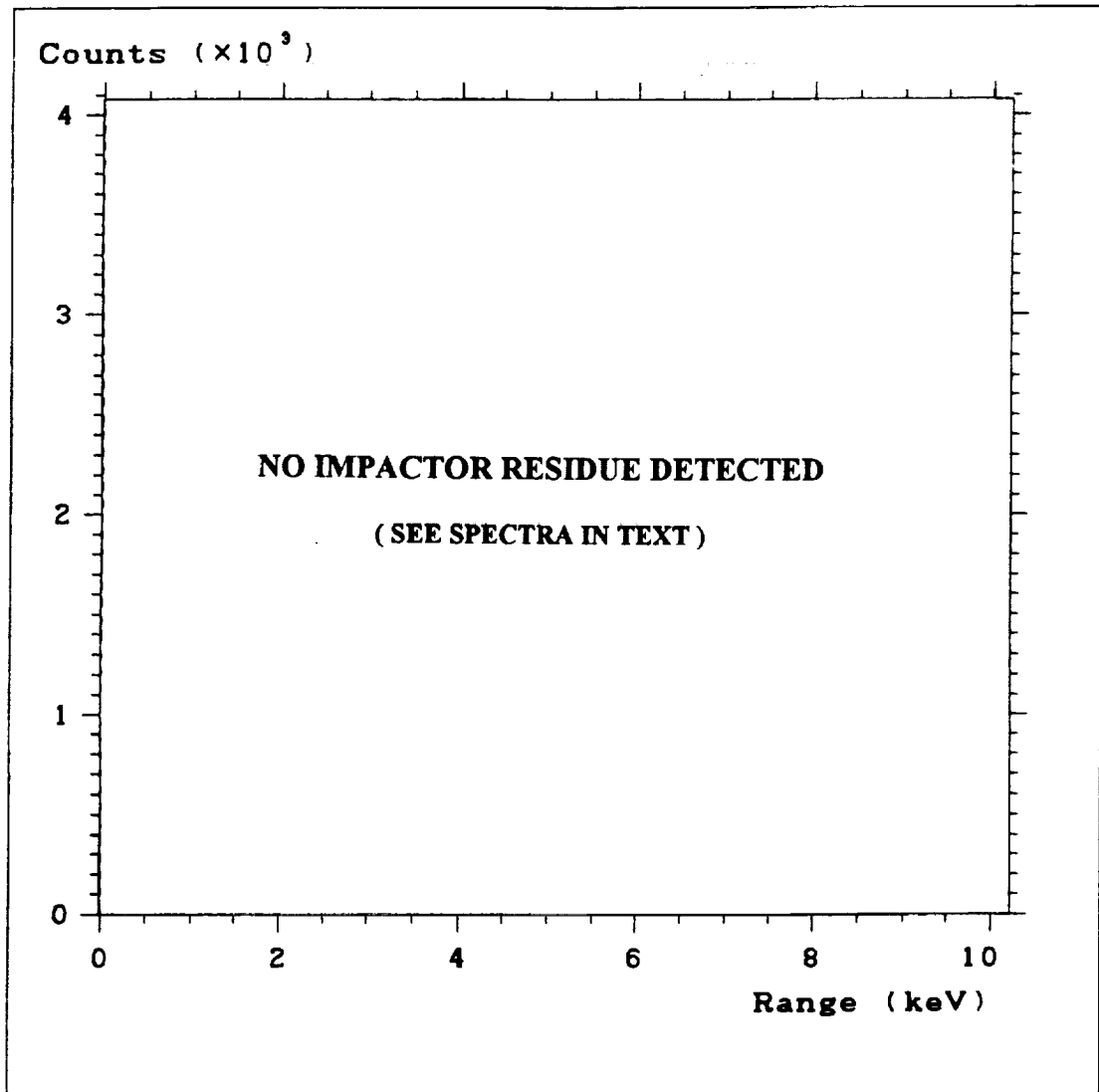


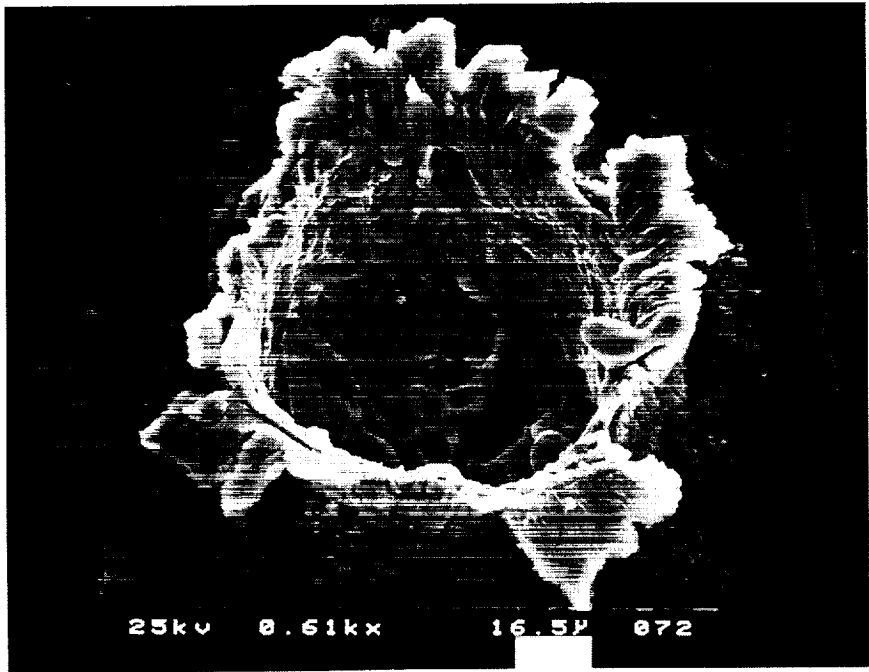
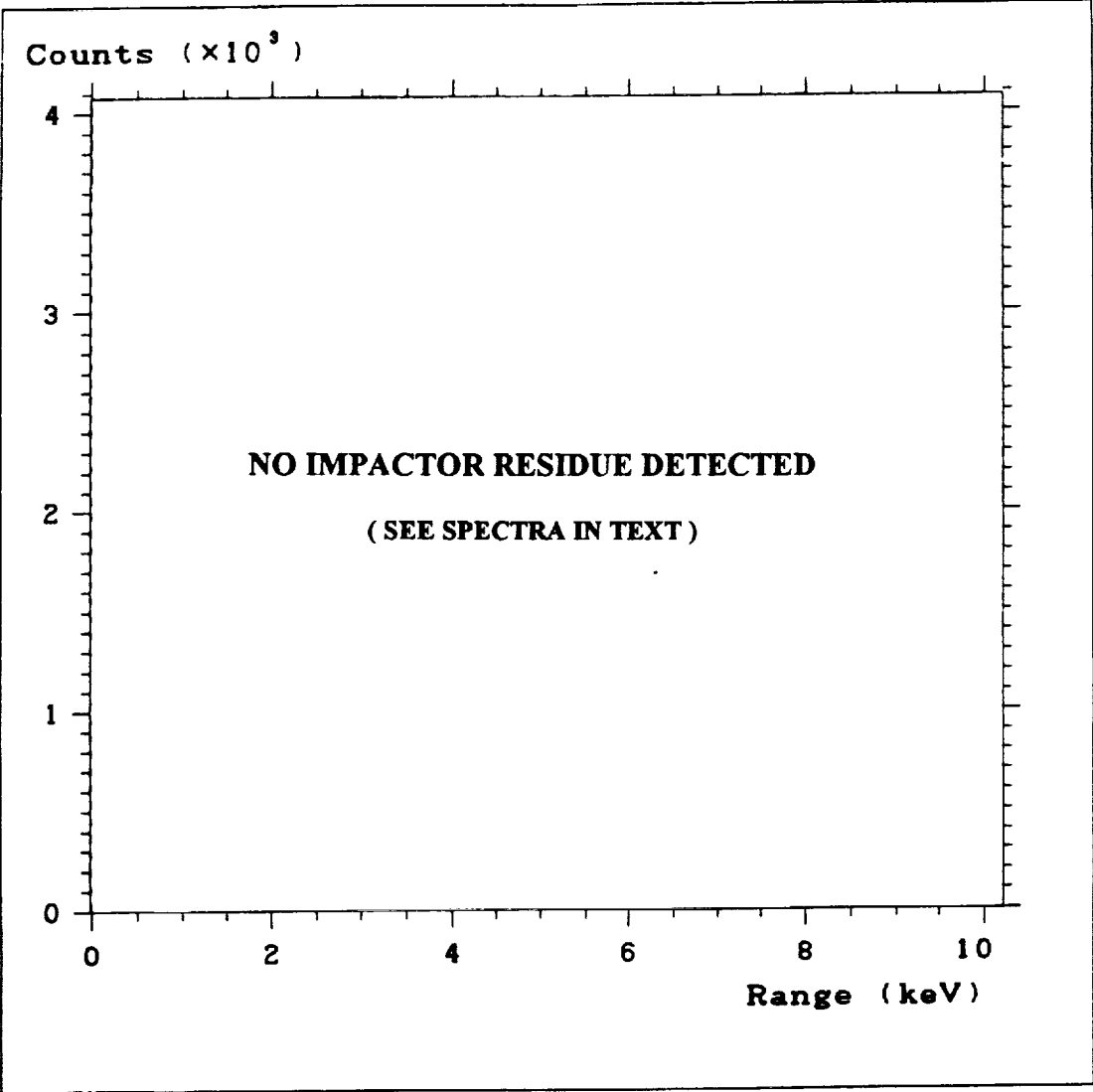


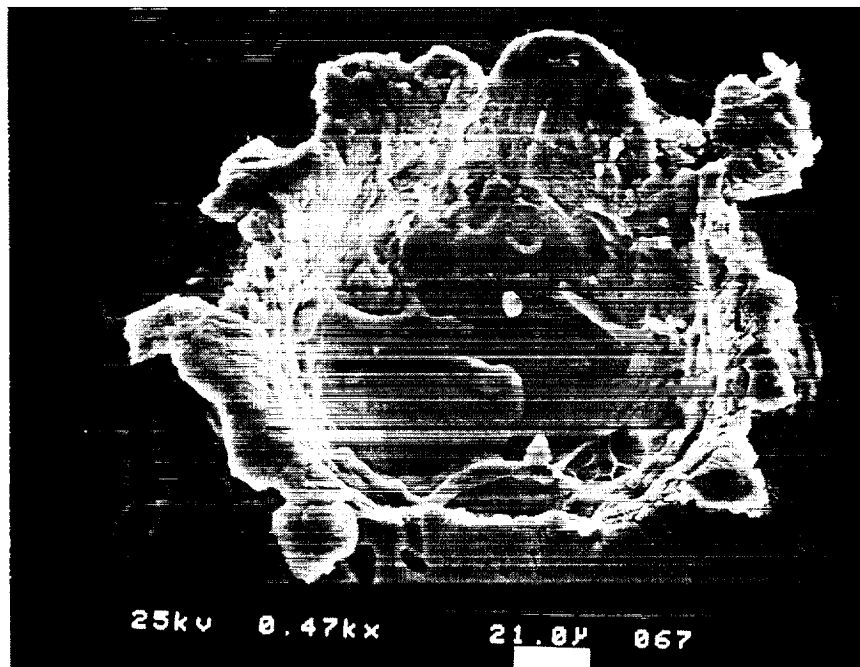
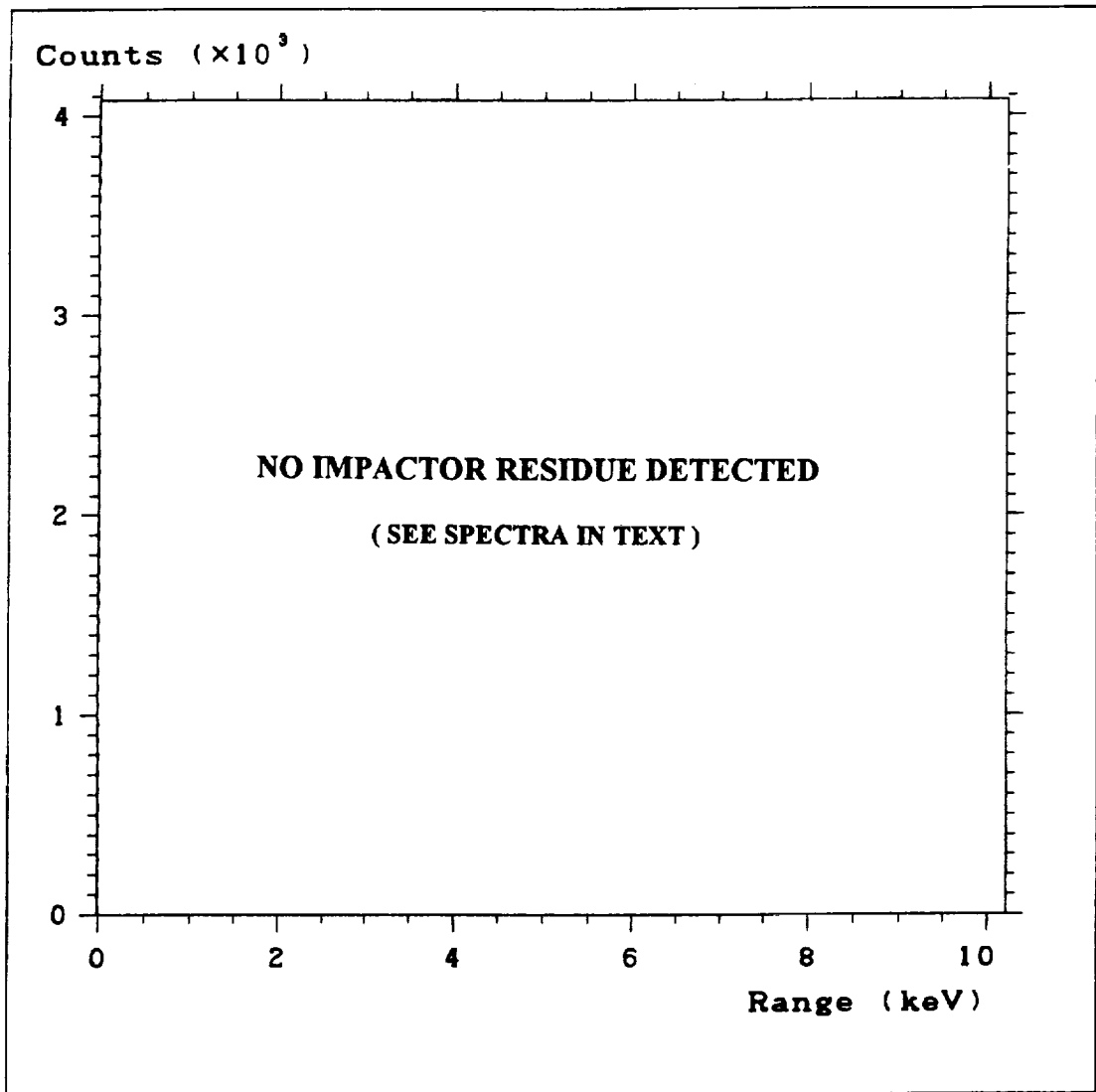


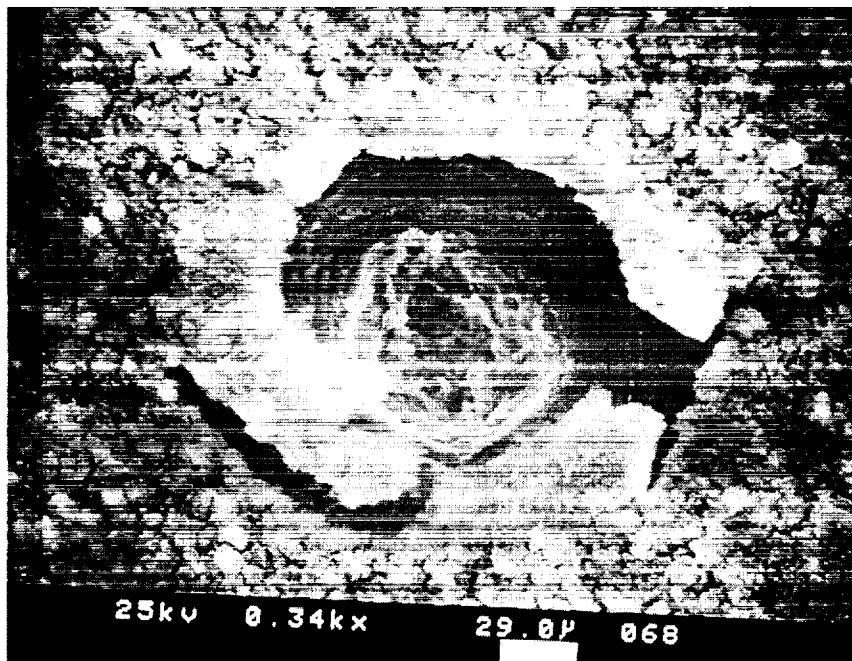
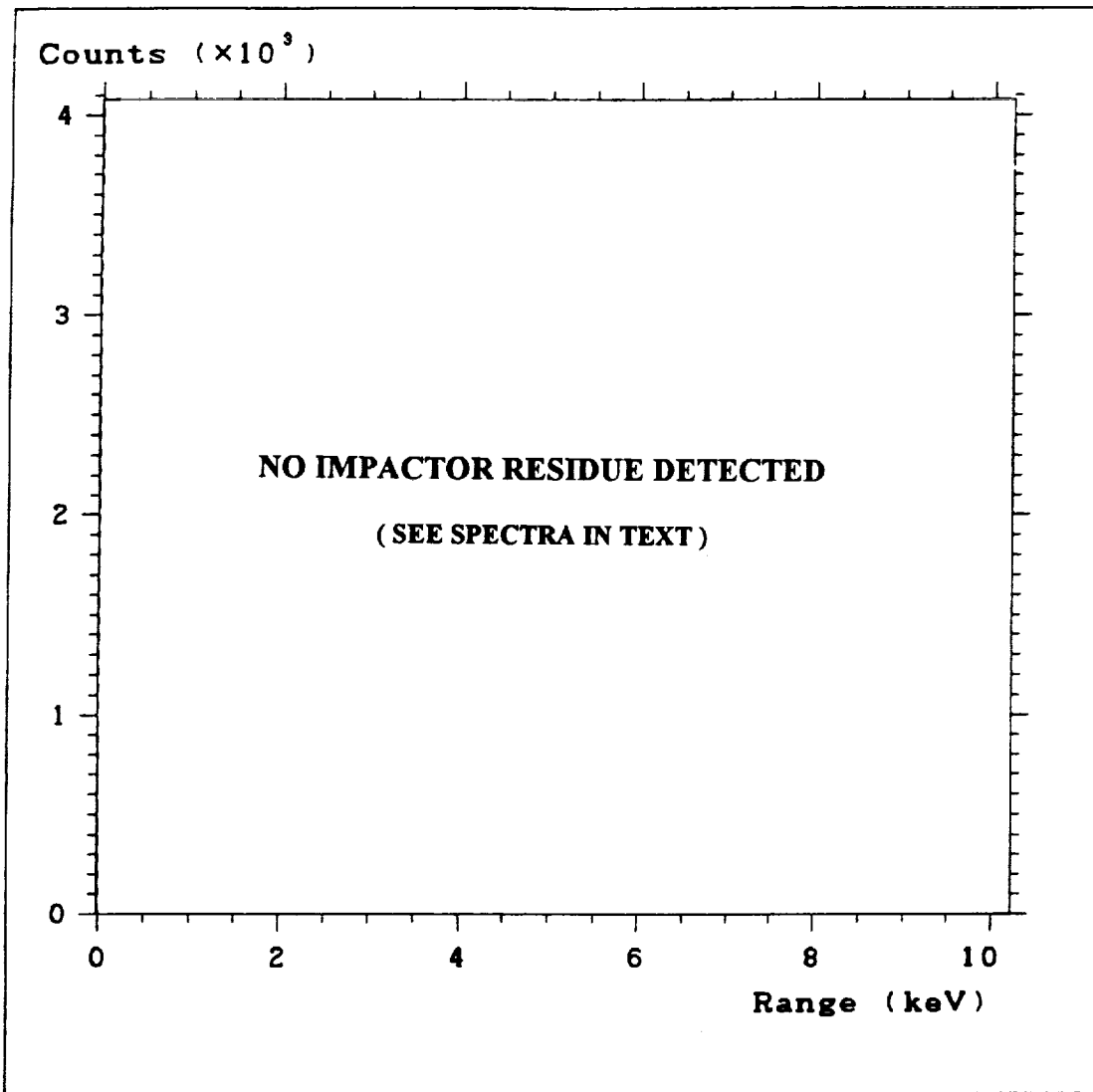


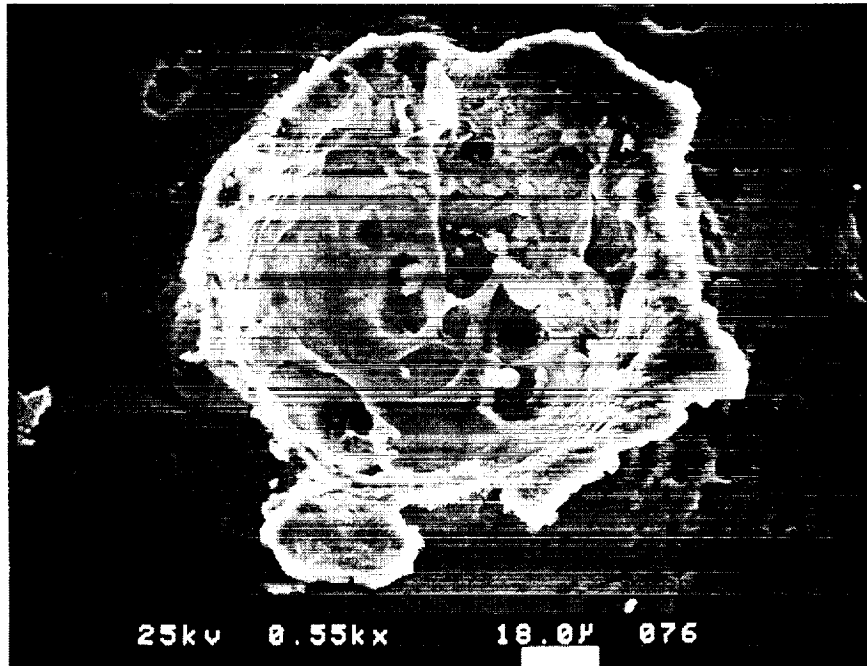
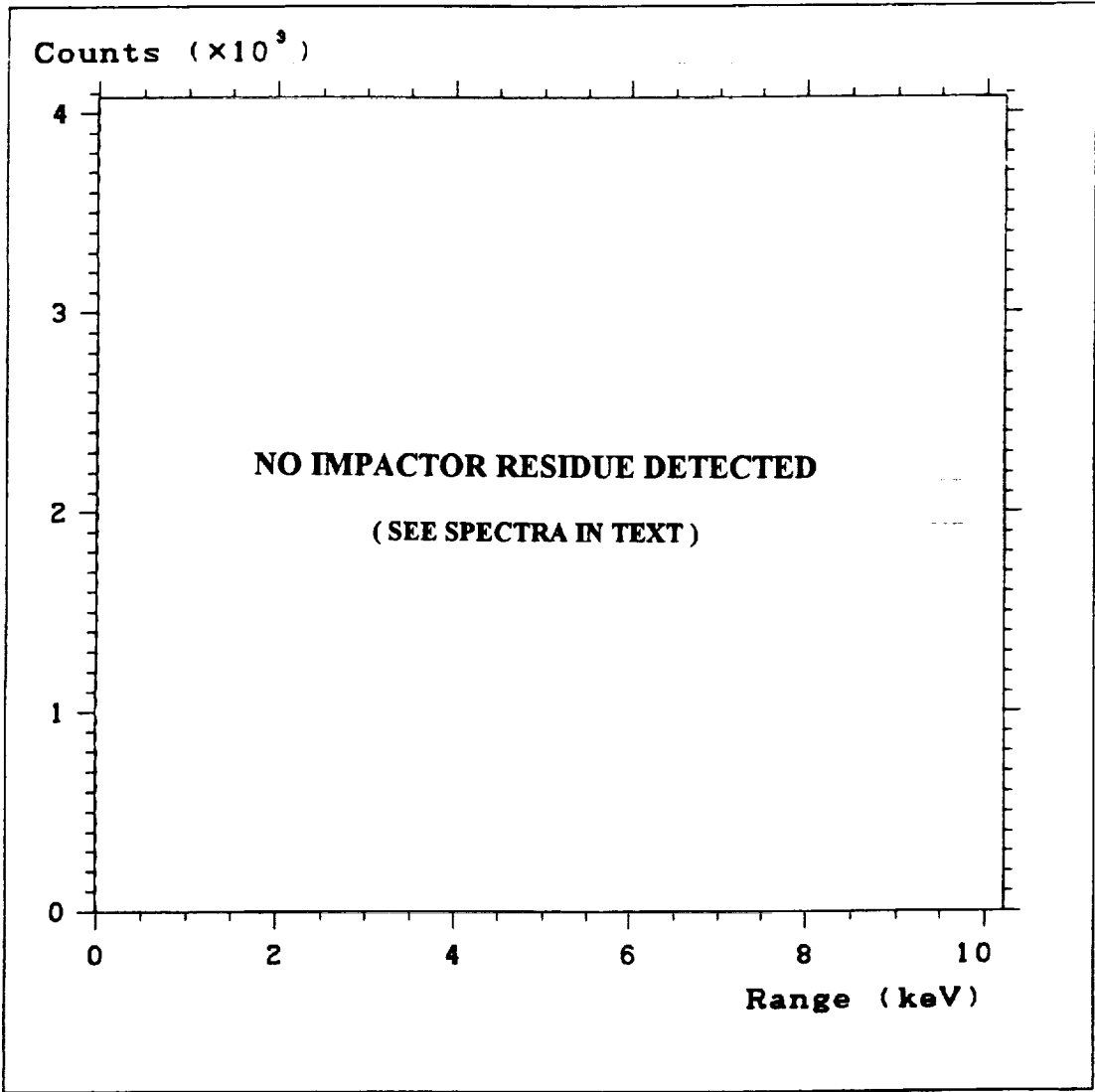






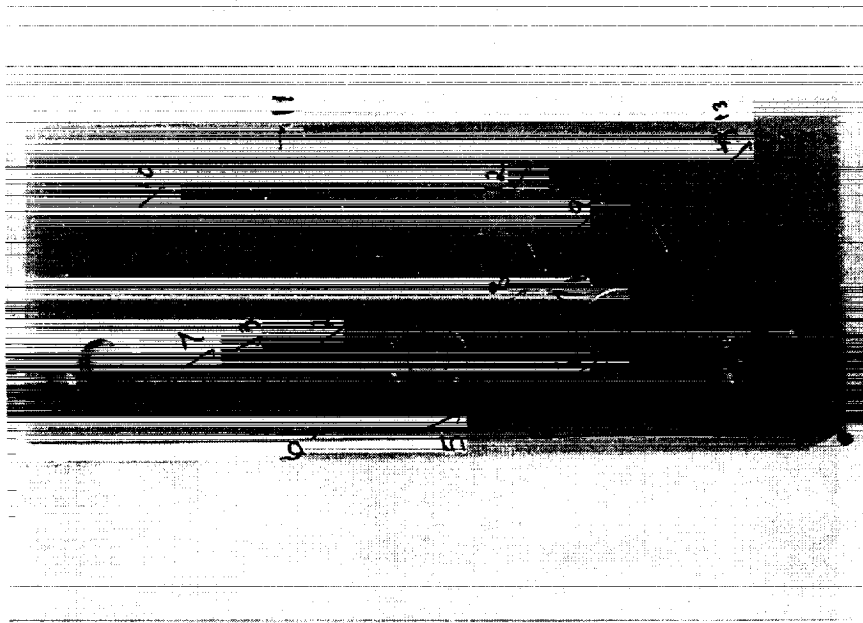


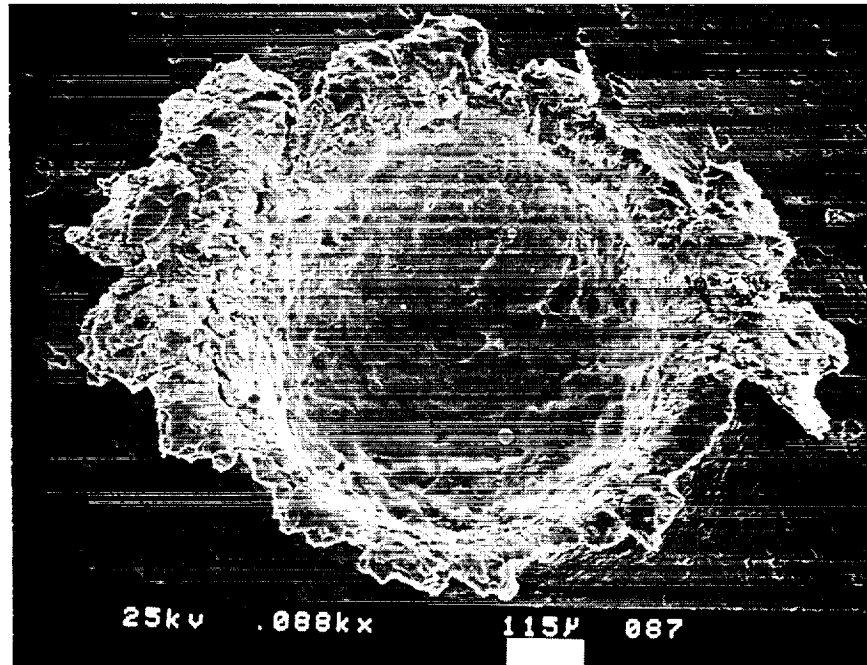
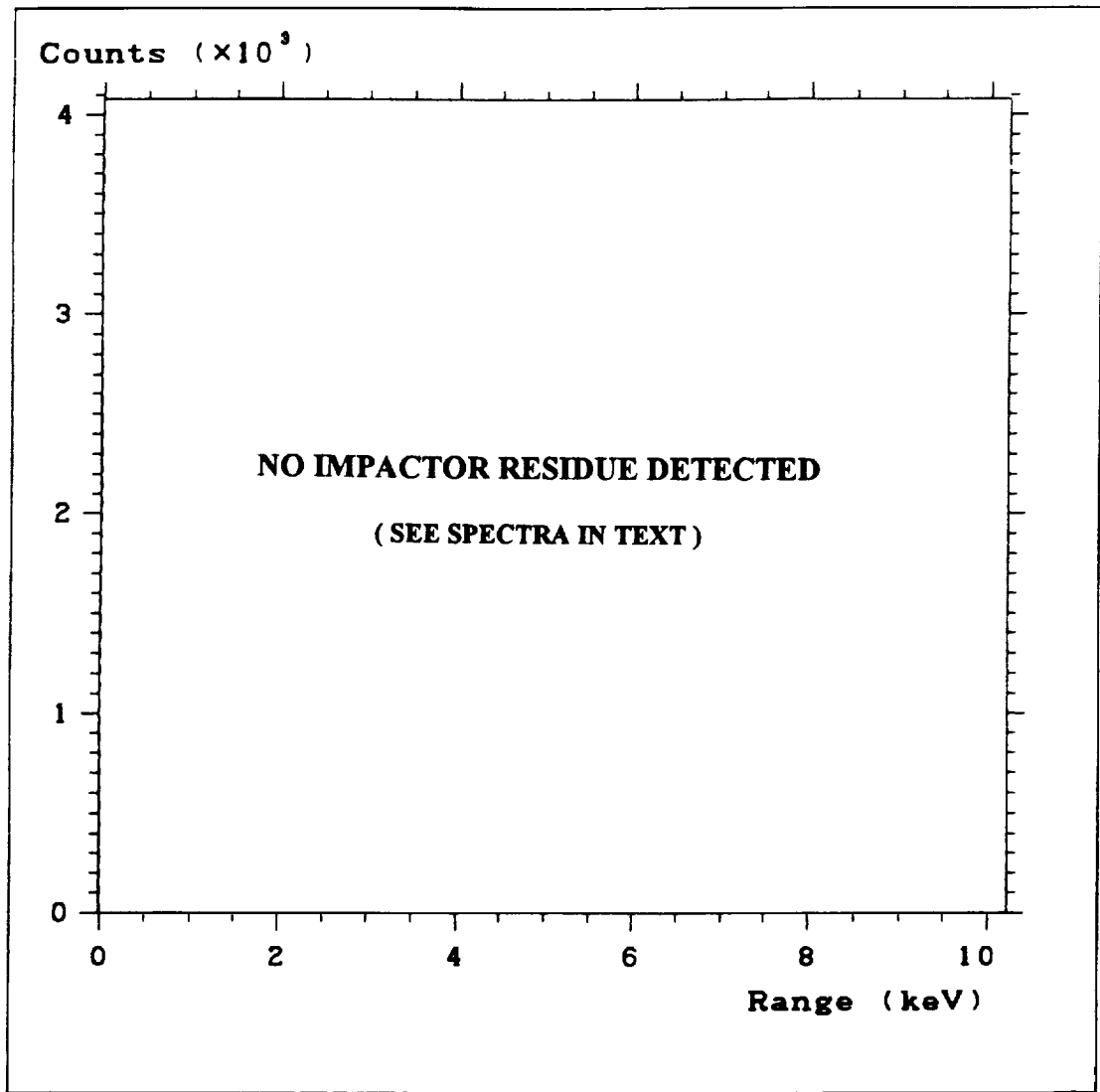


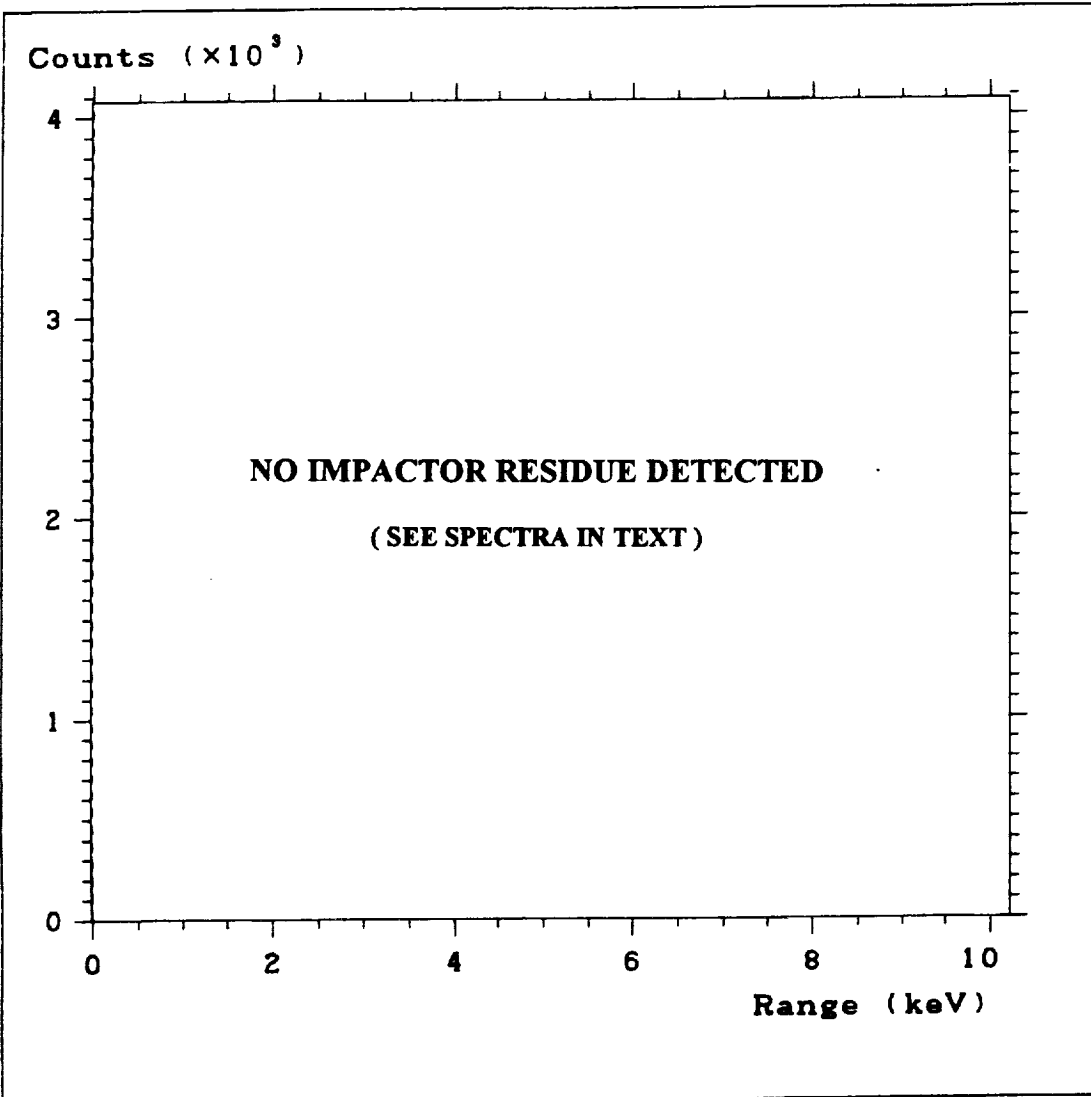


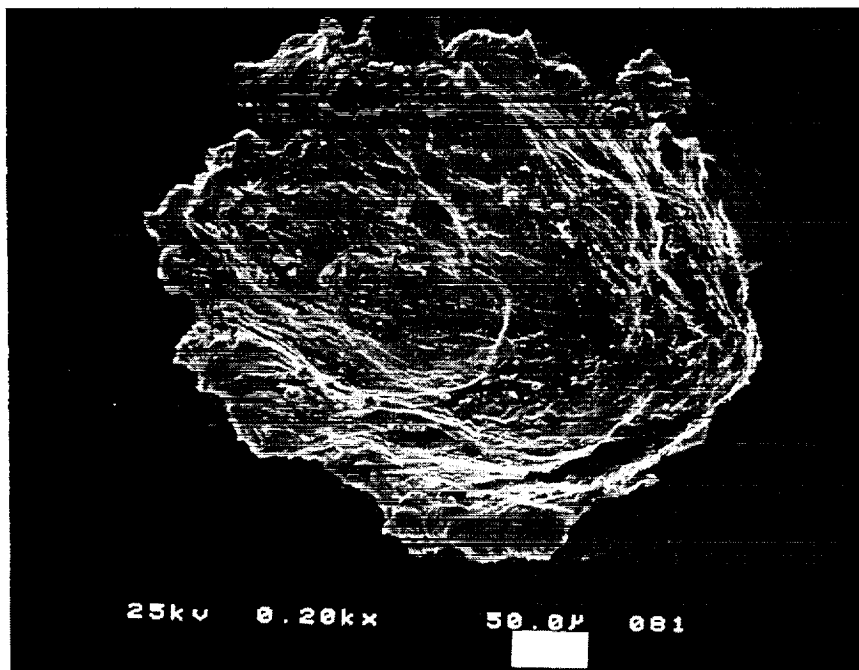
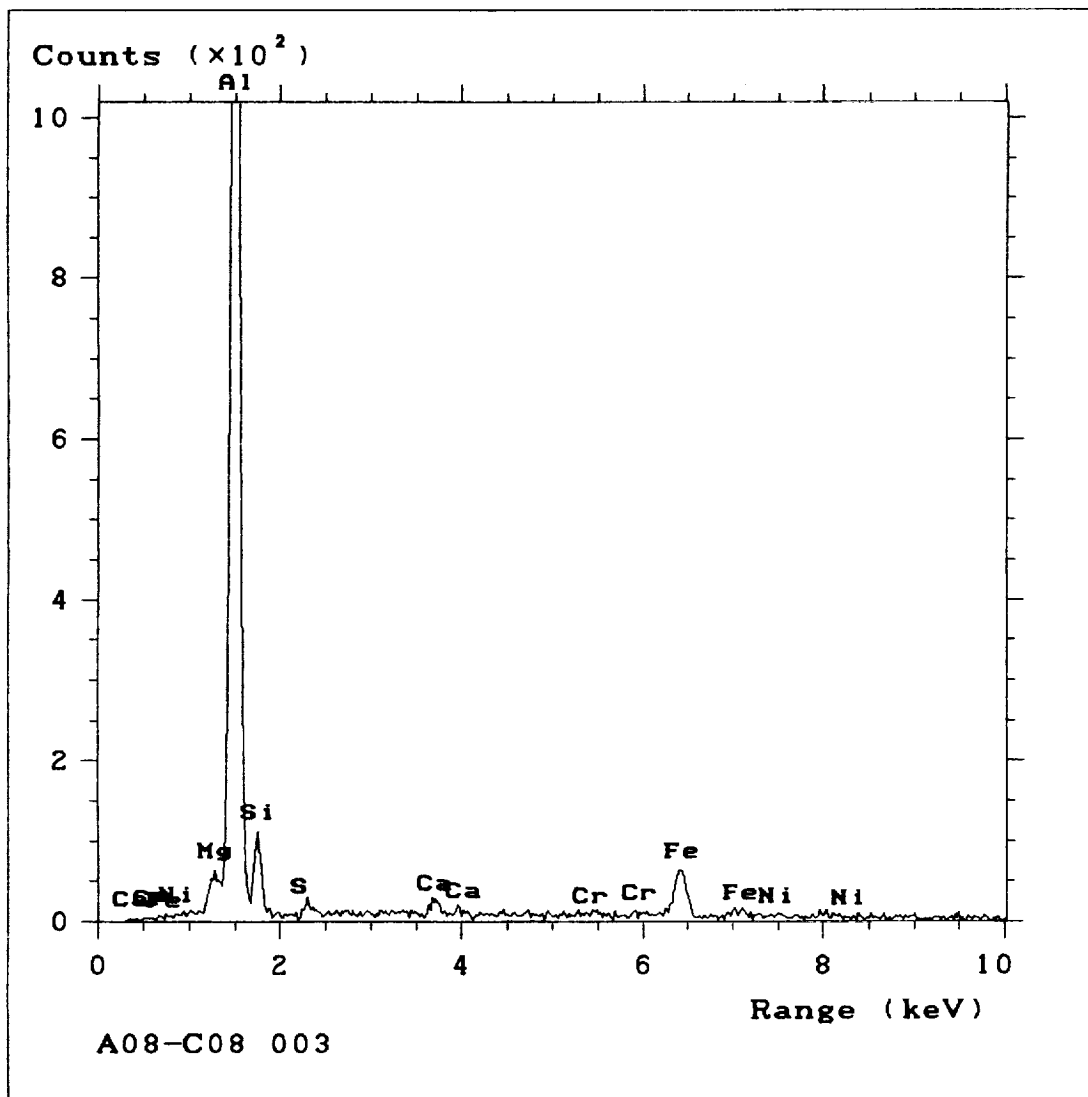
CLAMP NUMBER A08 CO8

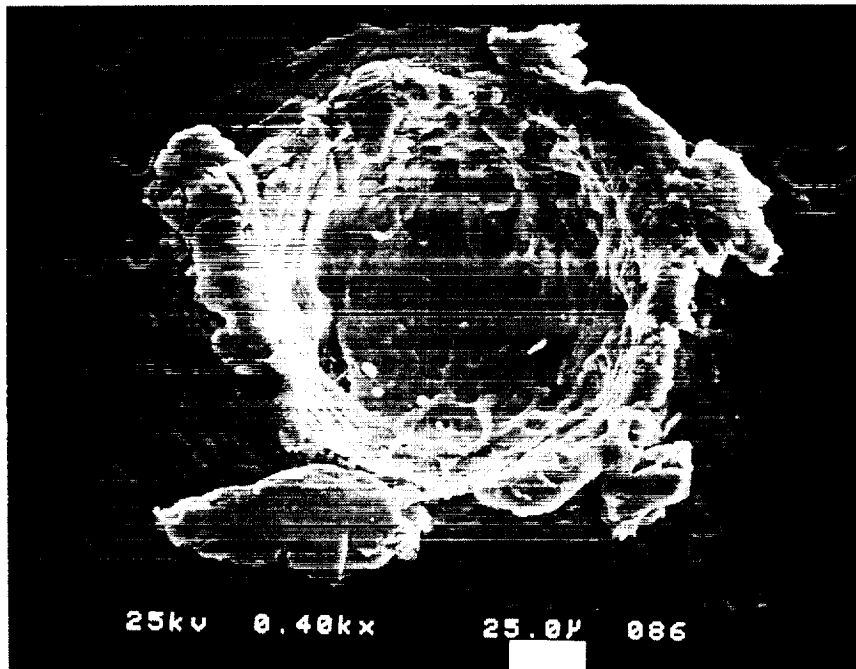
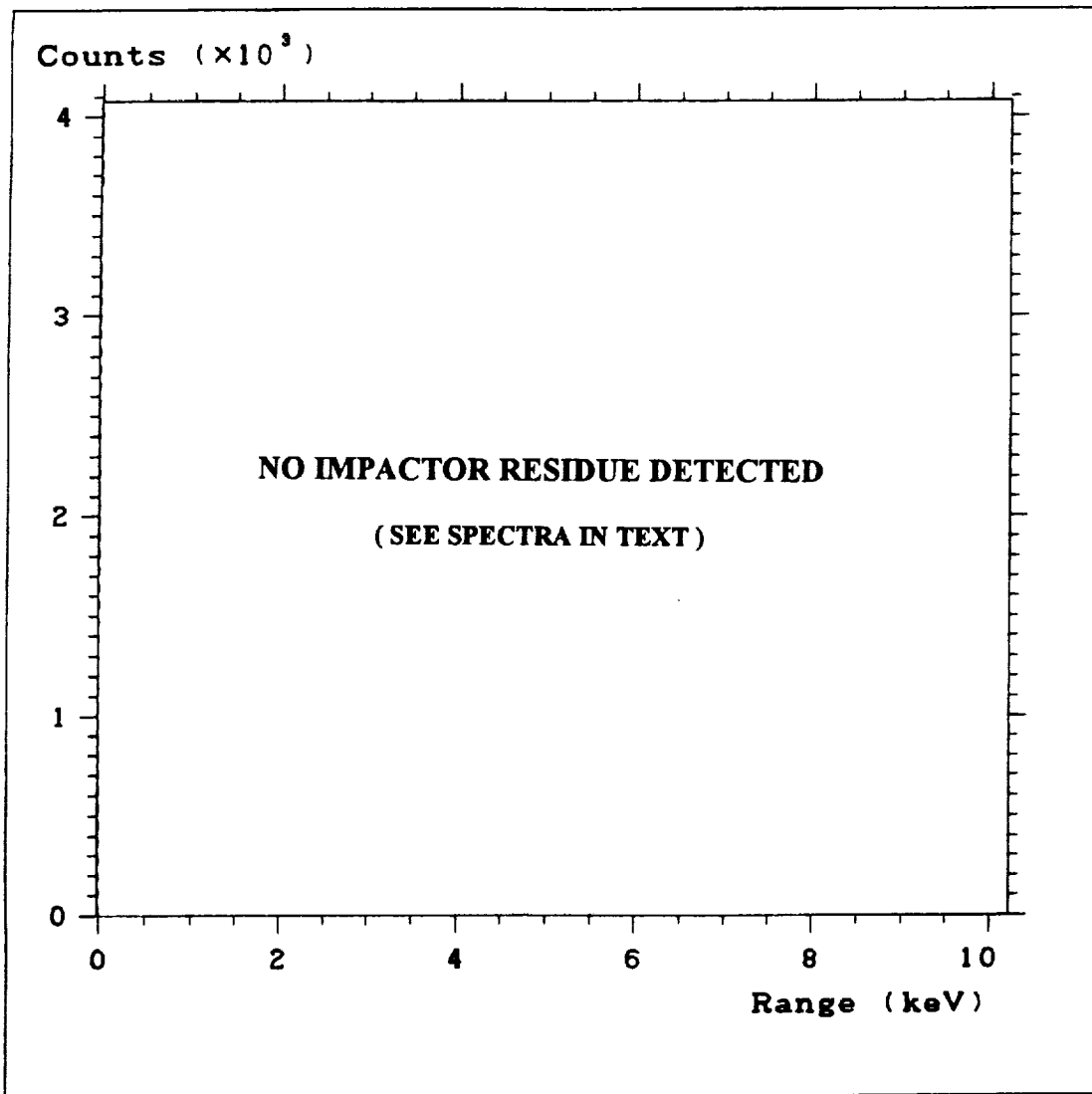
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	700	Unknown
002	500	Unknown
003	500	Trace
004	150	Unknown
005	200	Unknown
006	120	Si, Mg, Ca, Fe
007	190	Unknown
008	90	Unknown
009	110	Unknown
010	100	Paint
011	400	Unknown
012	350	Si, Mg, Ca
013	120	Si, Mg, Ca

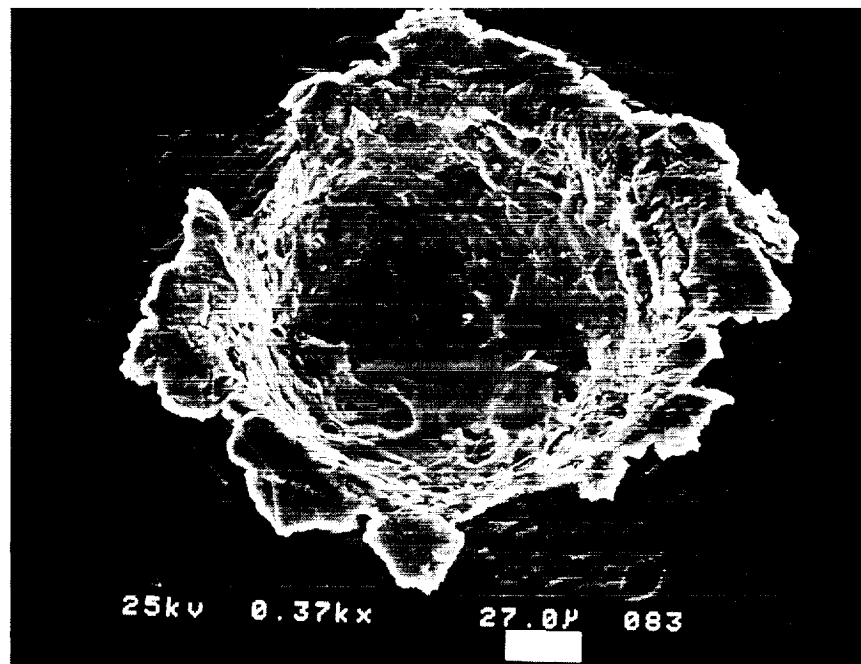
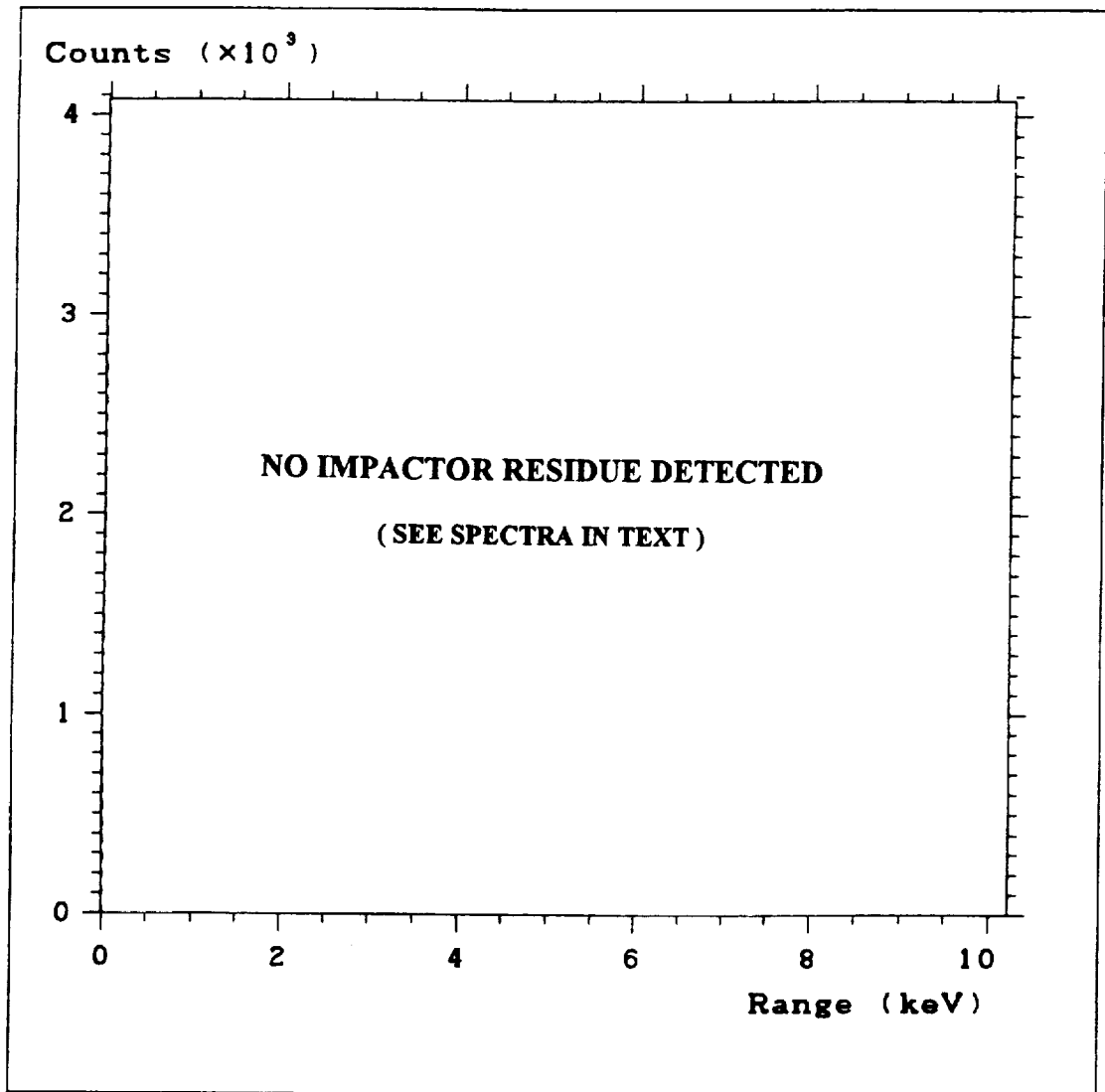


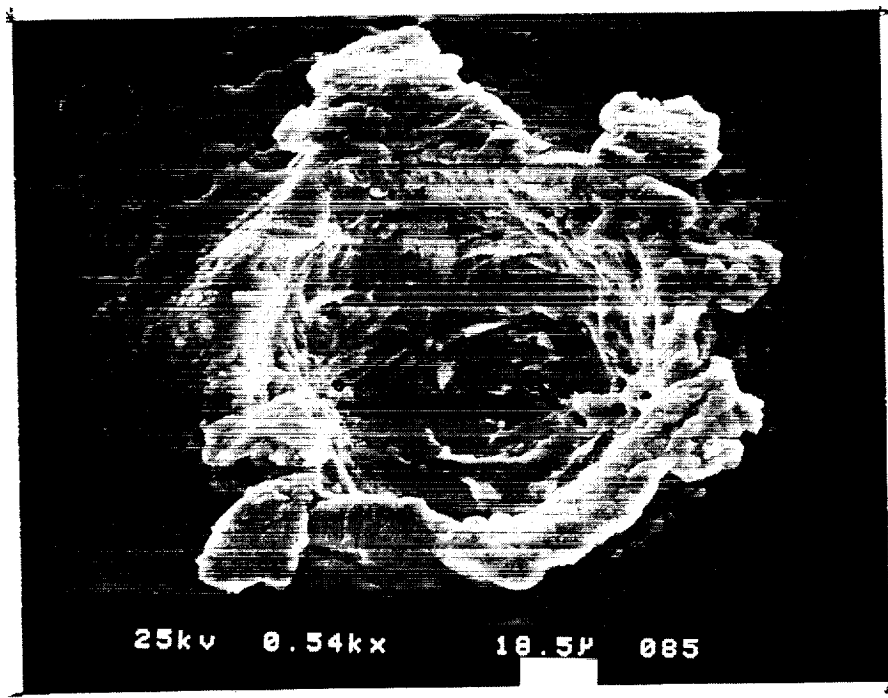
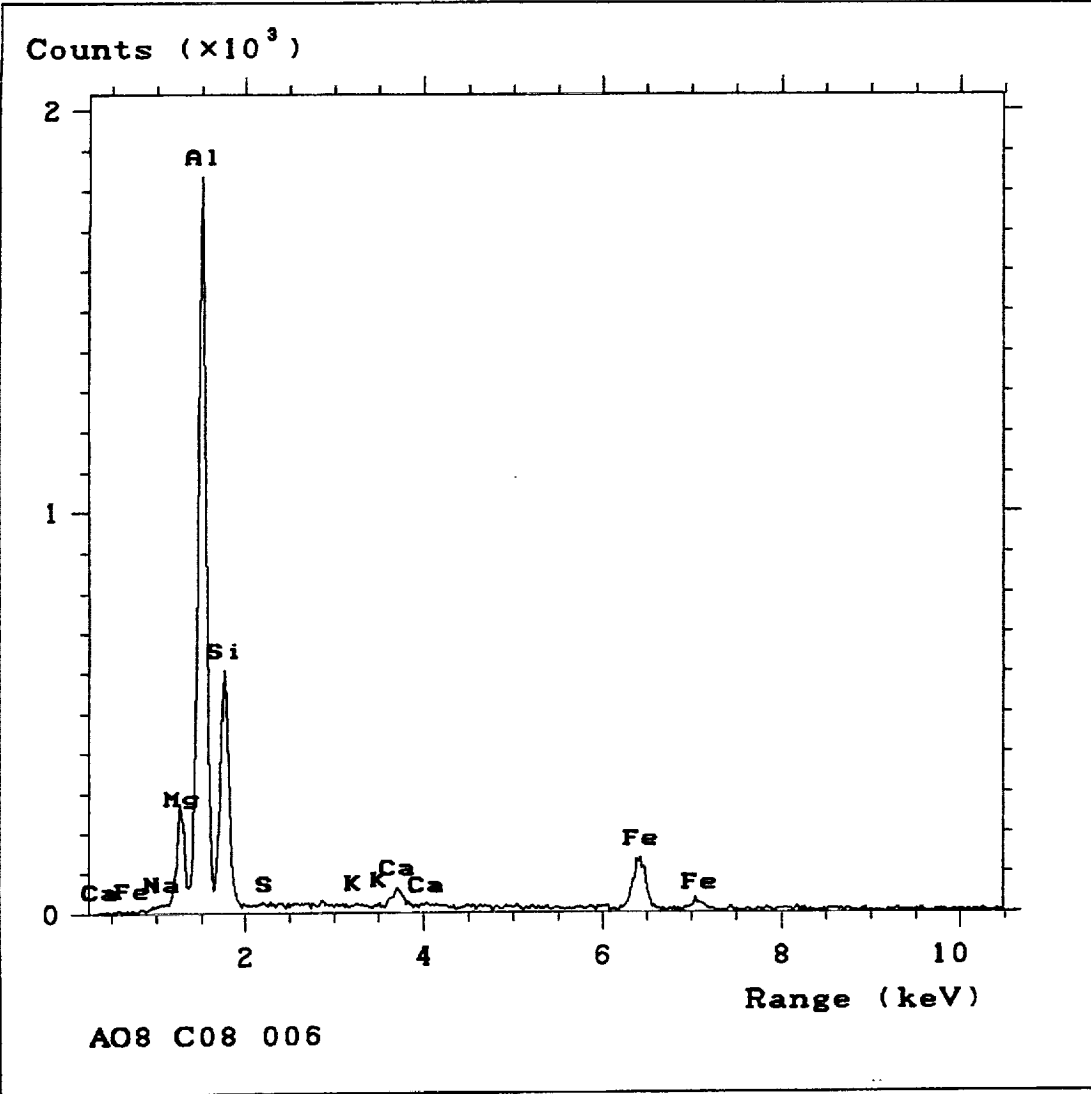


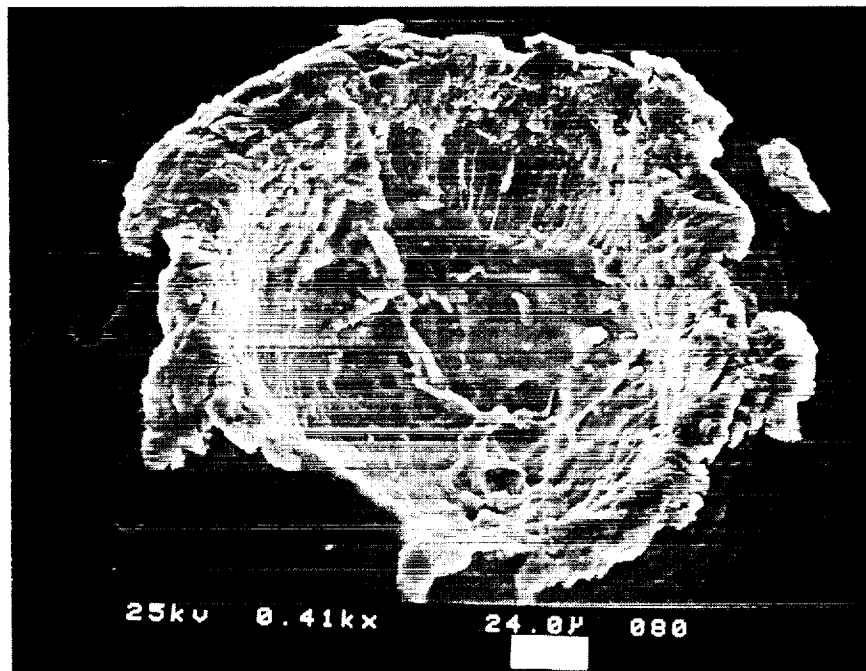
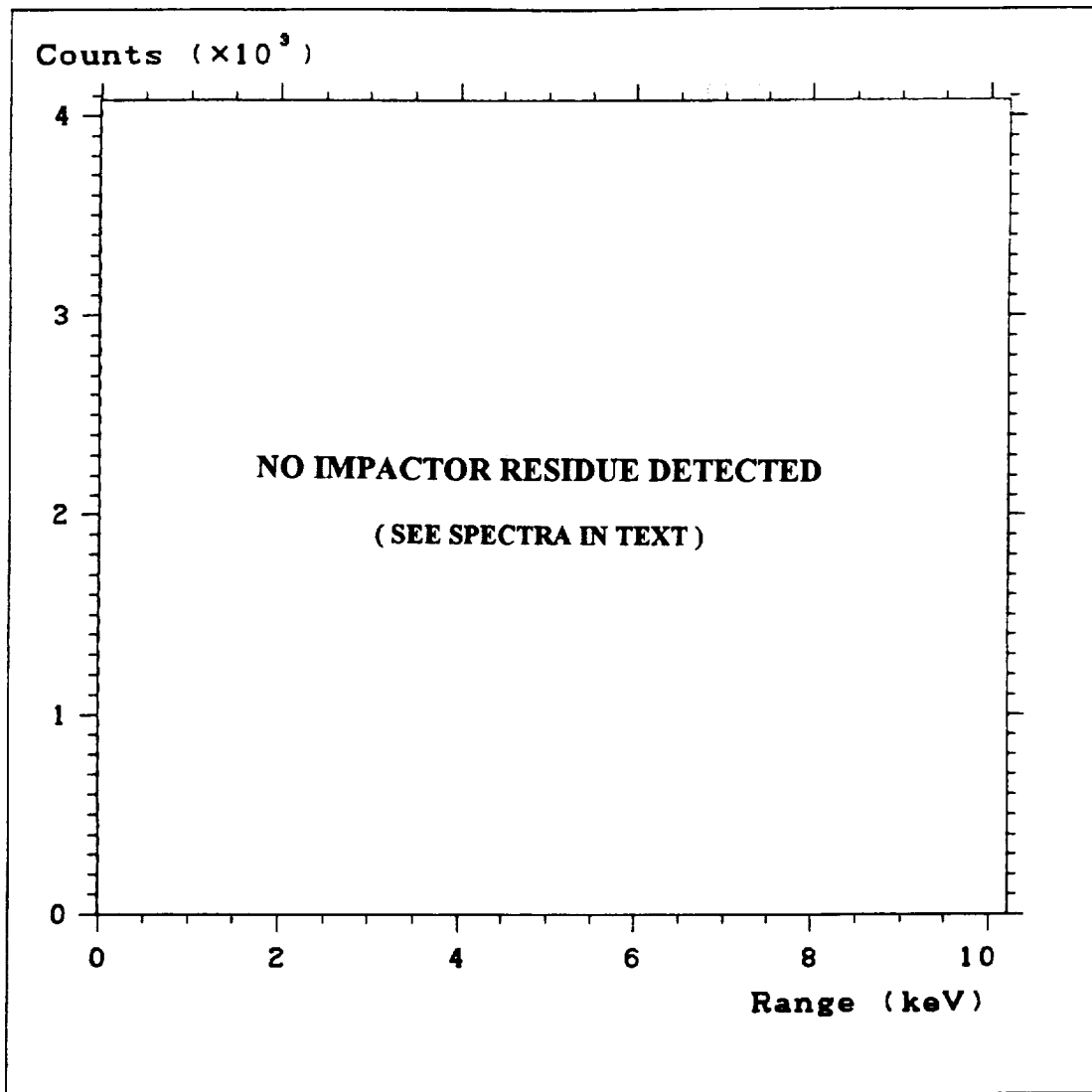


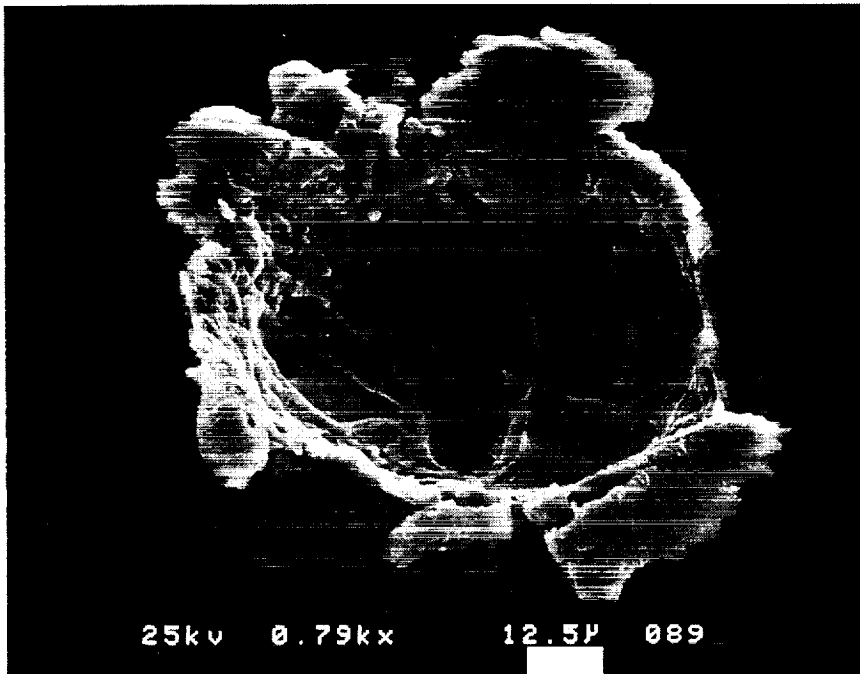
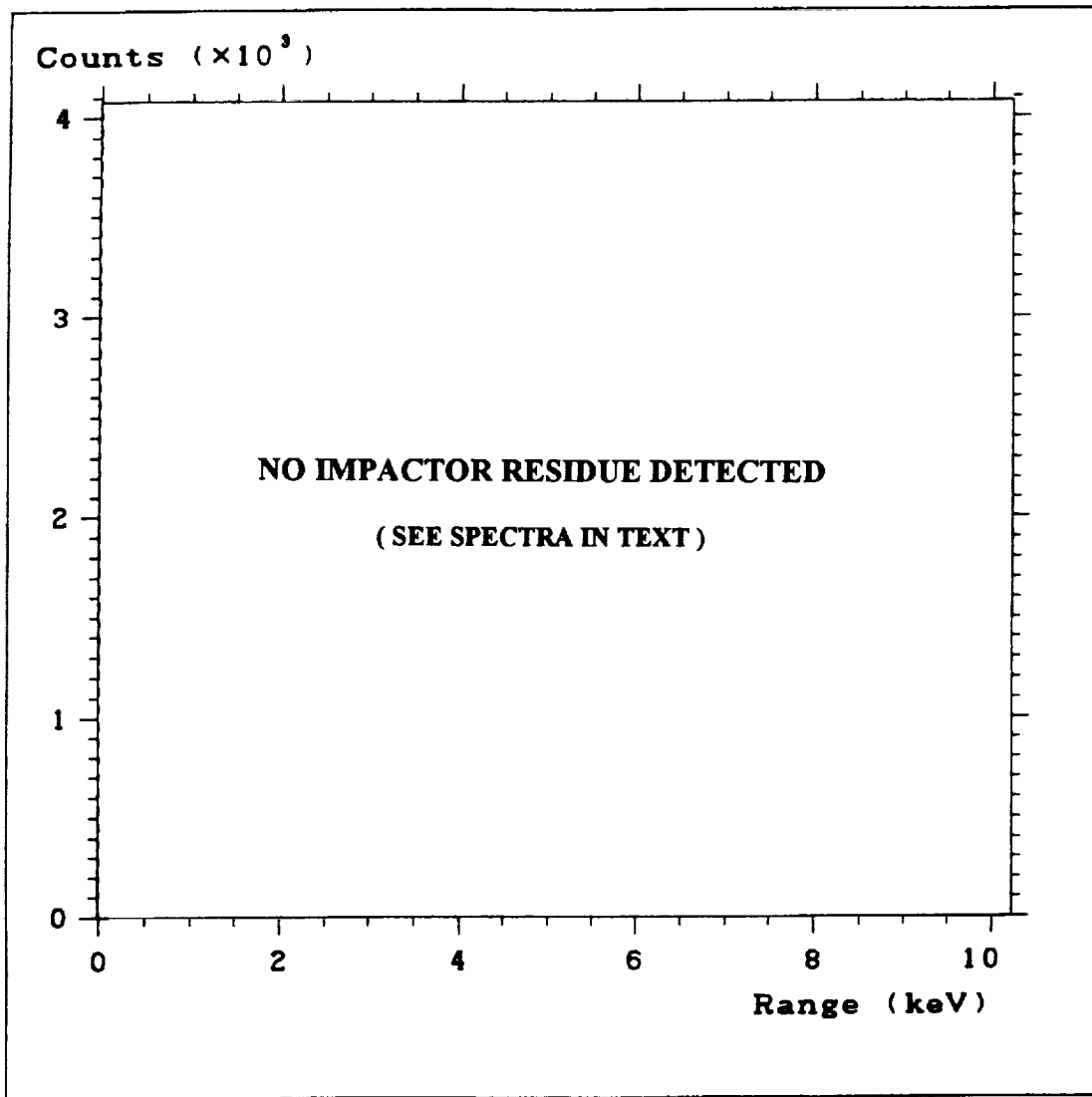


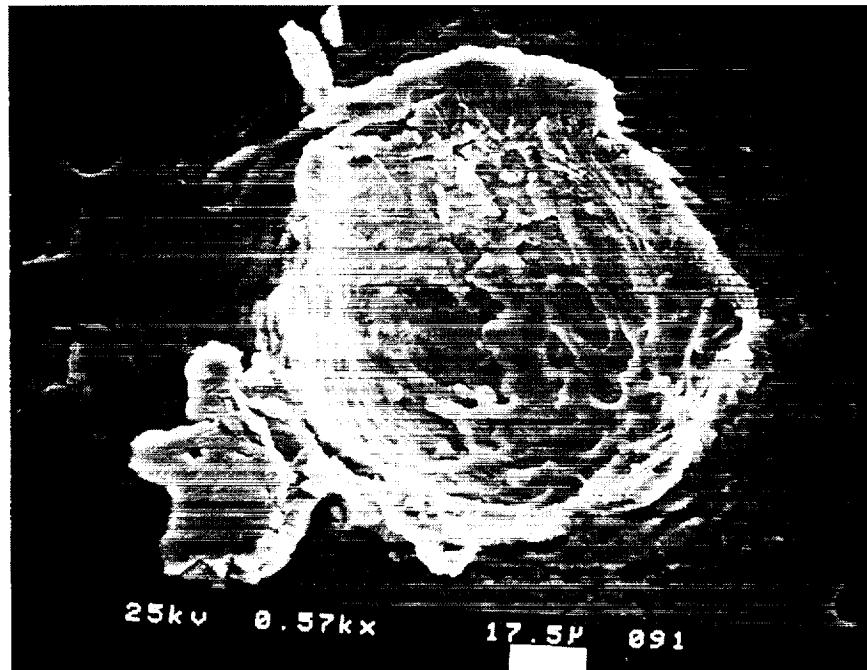
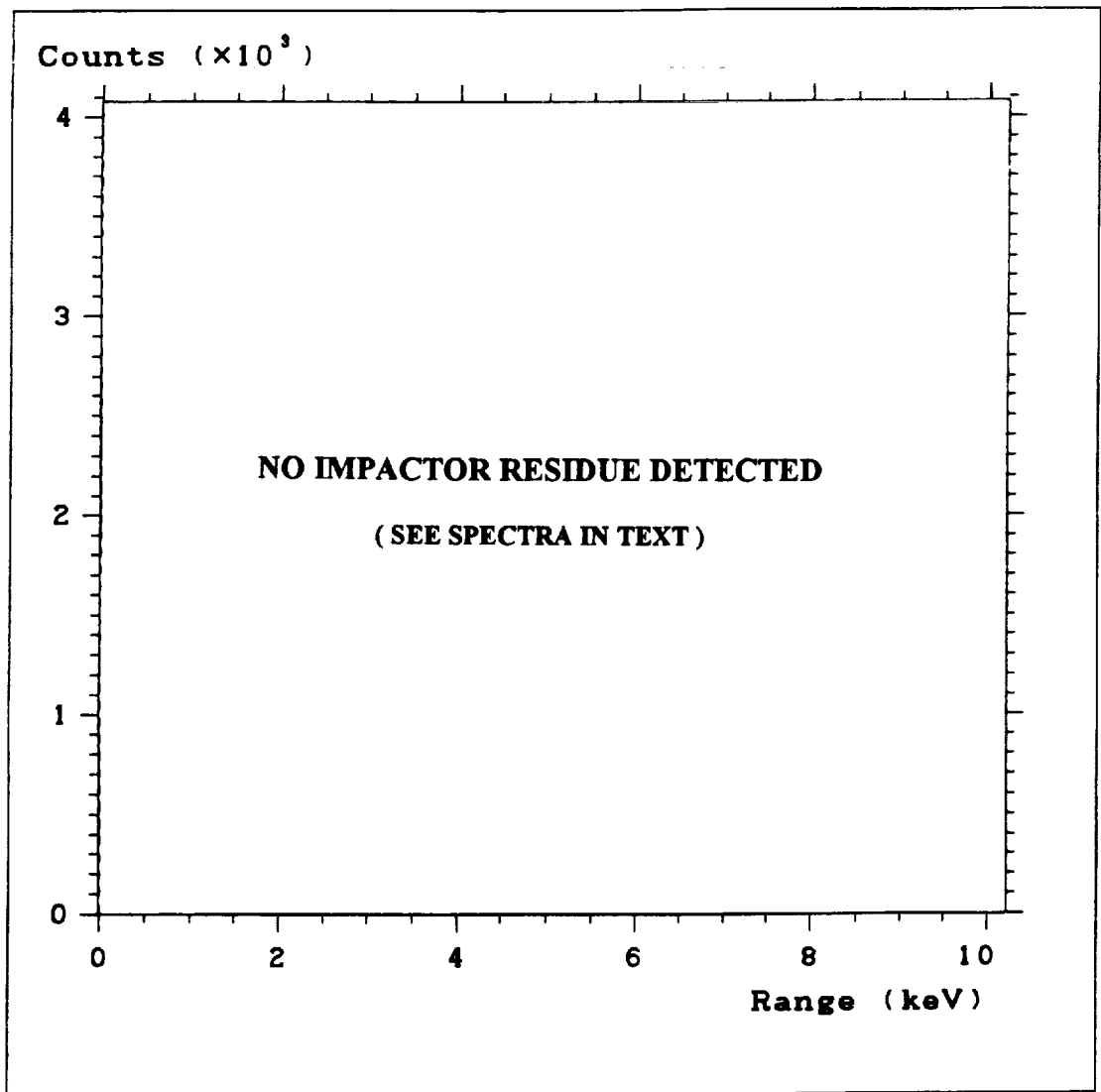


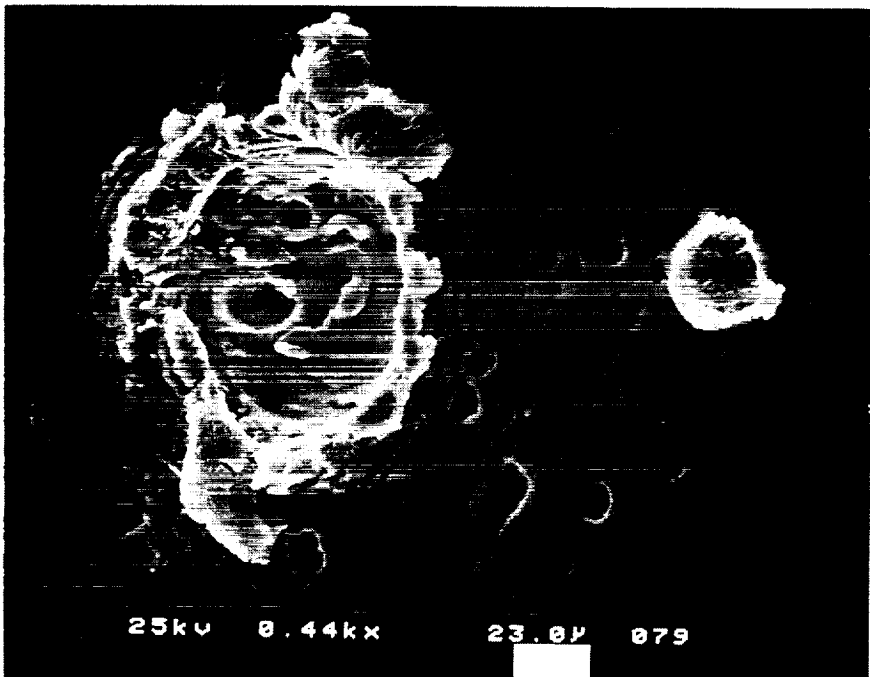
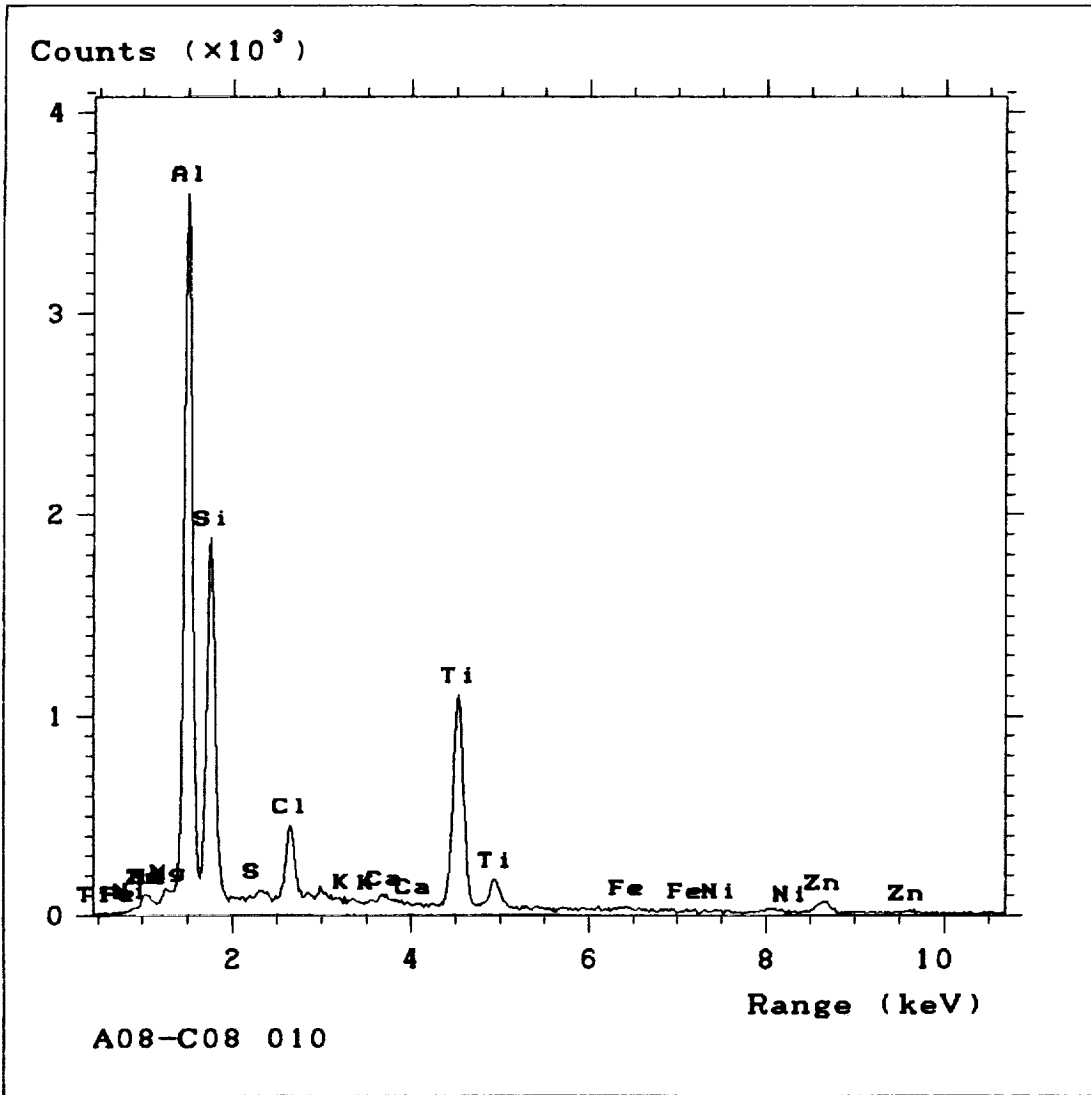


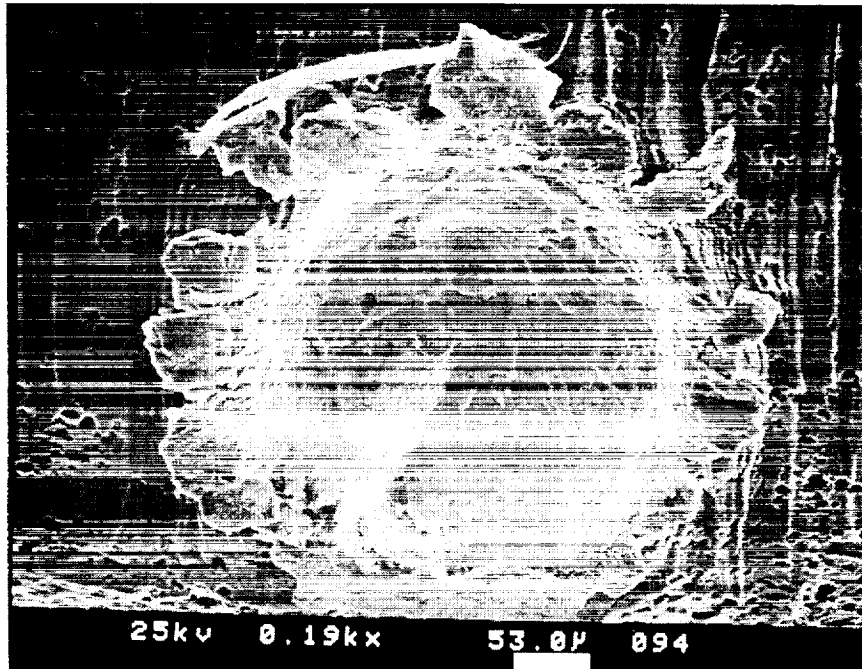
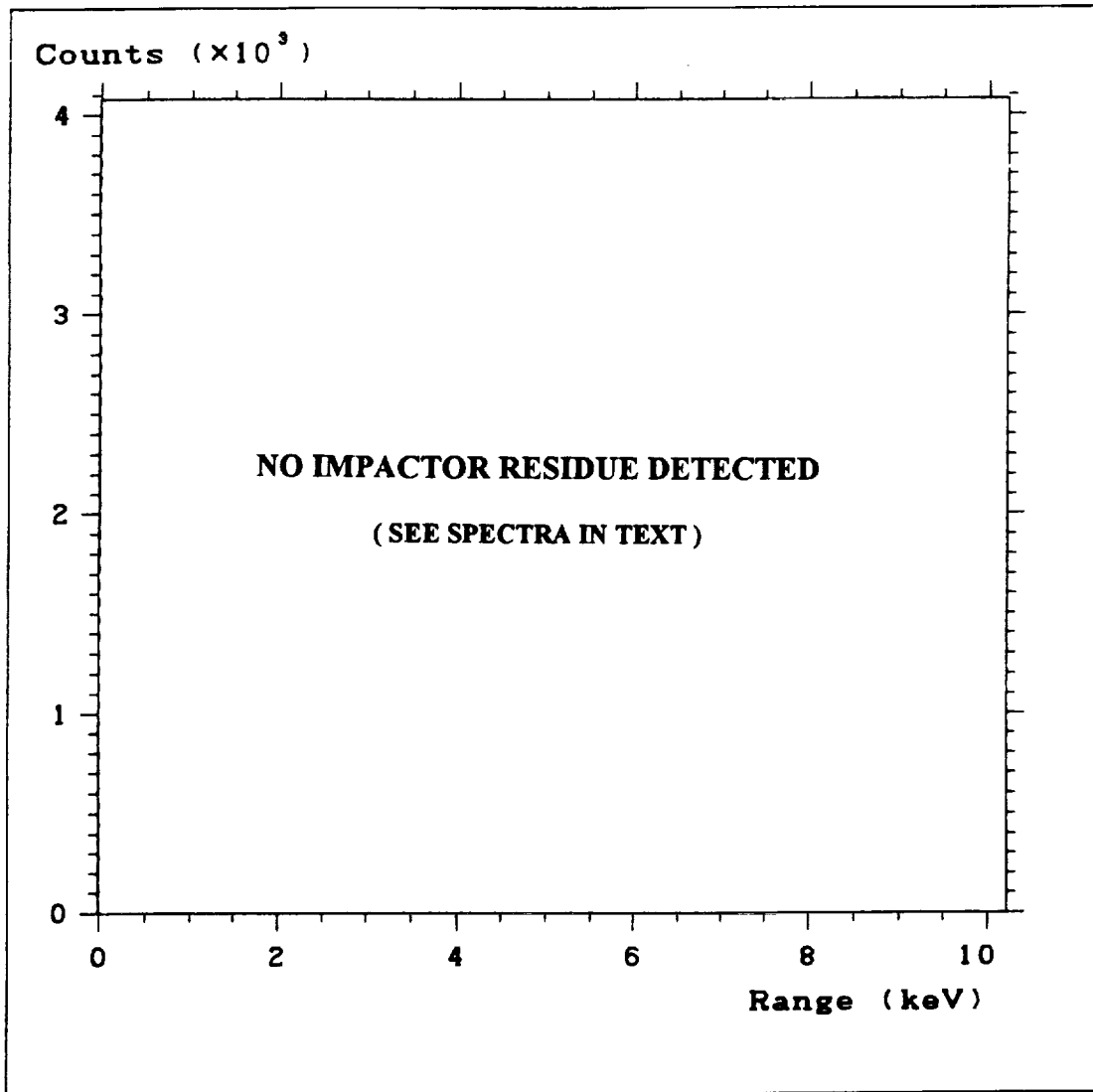


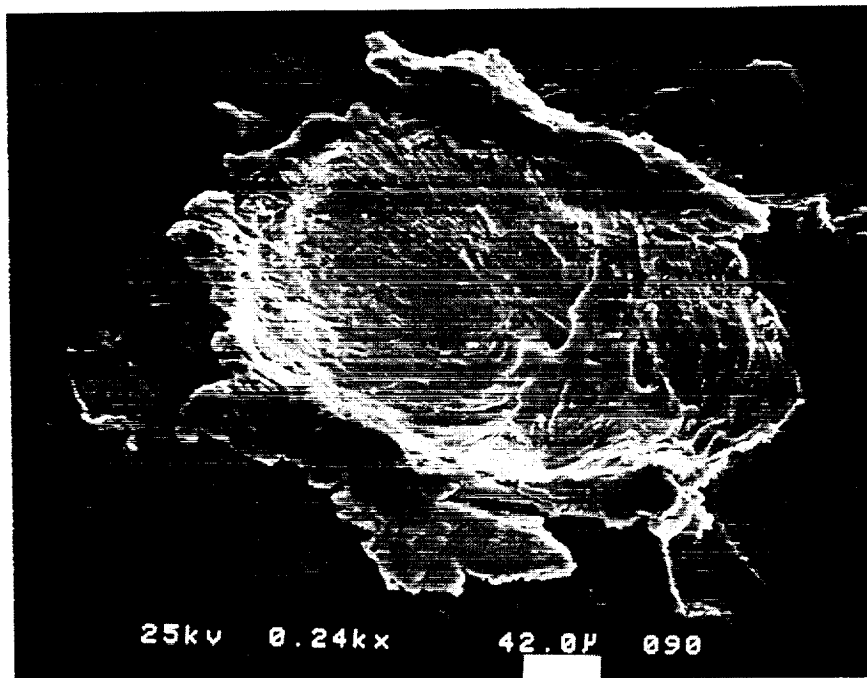
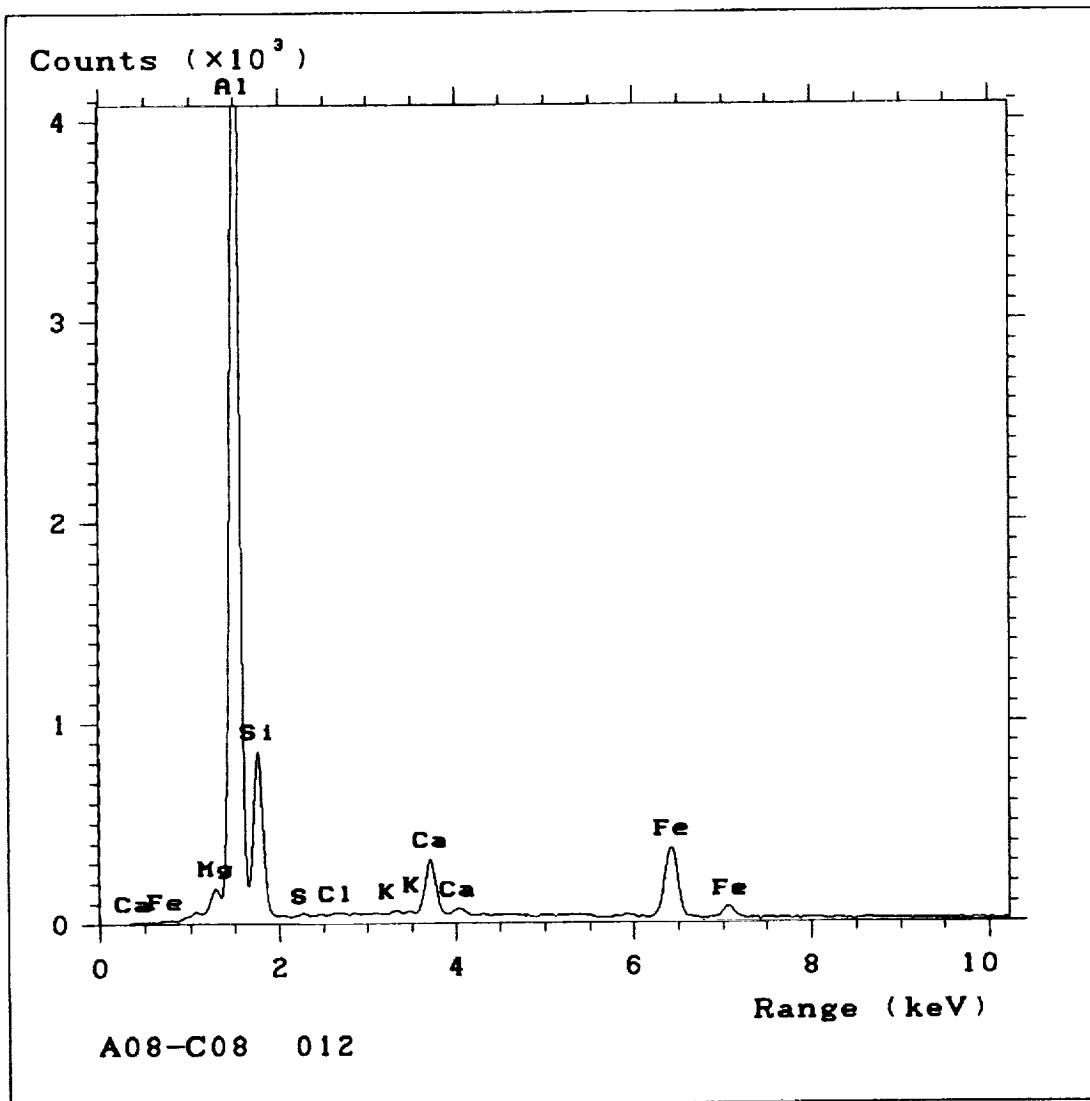


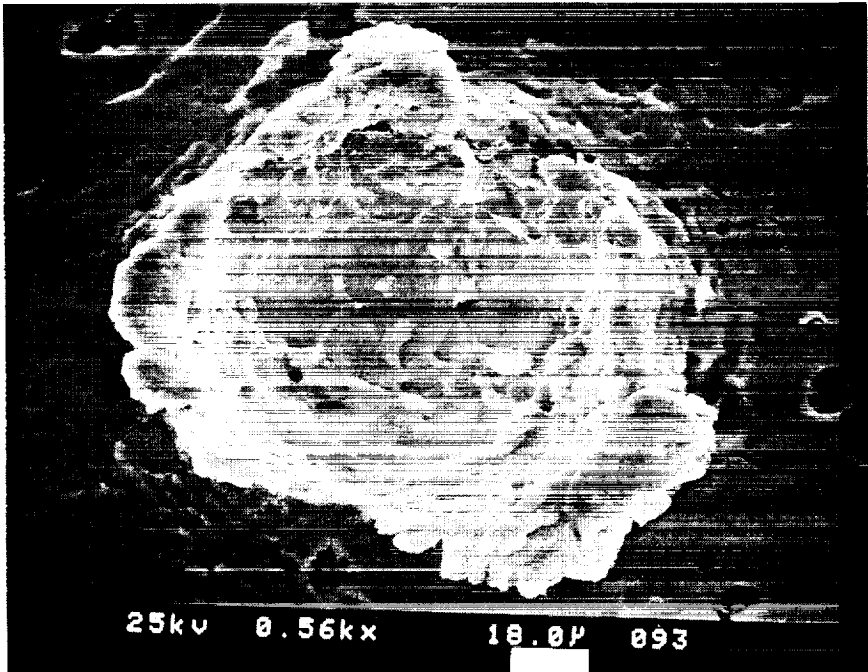
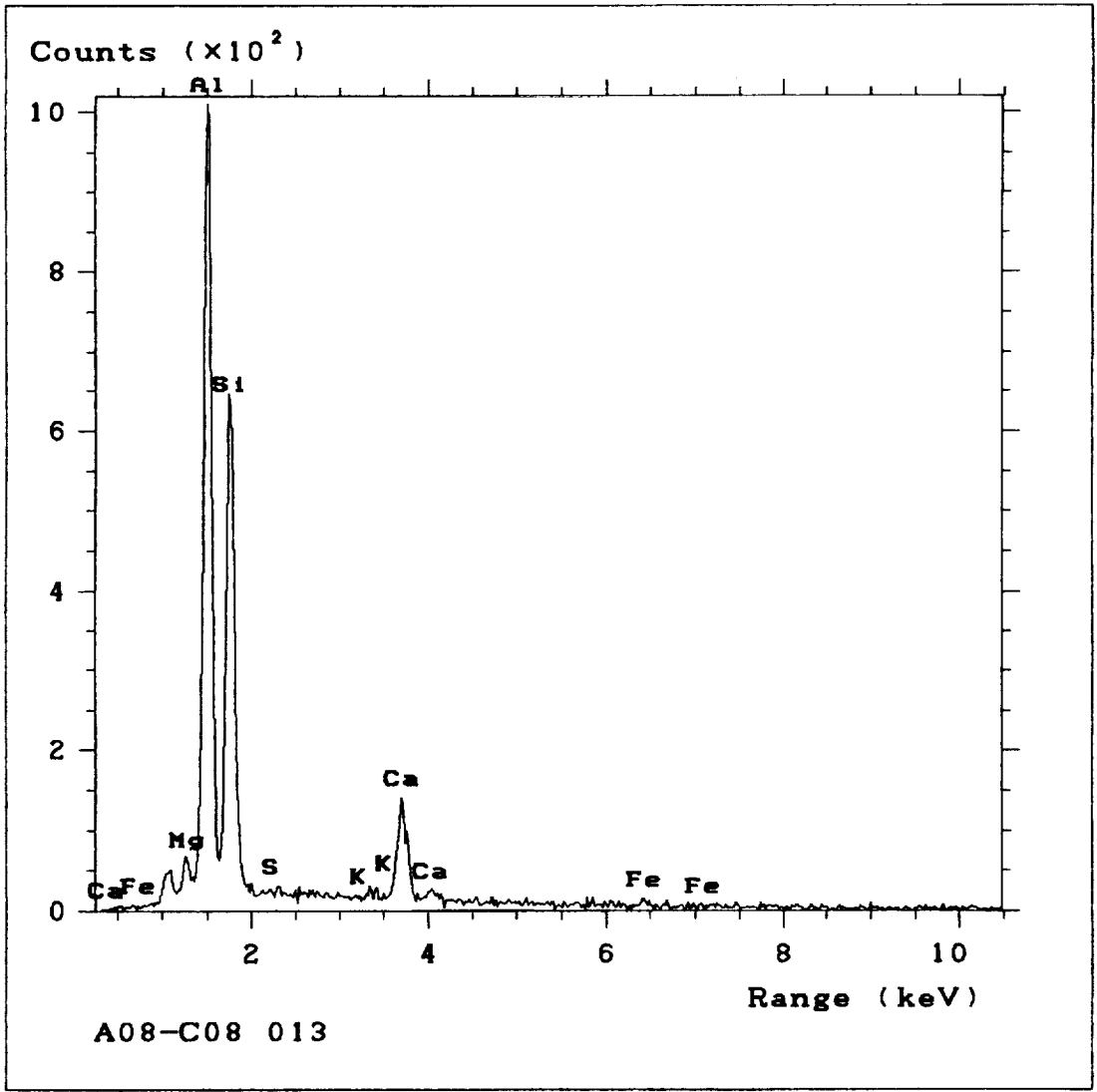






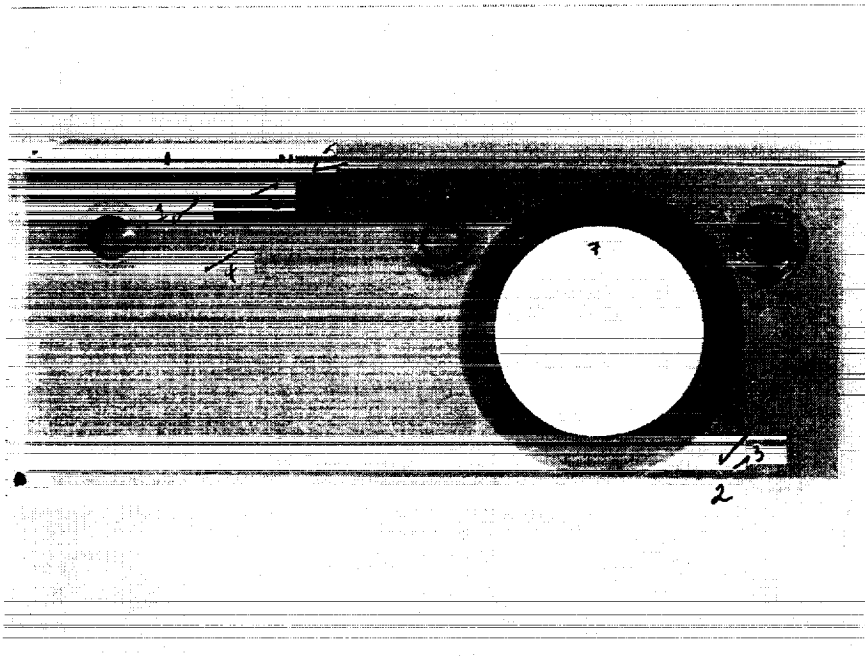


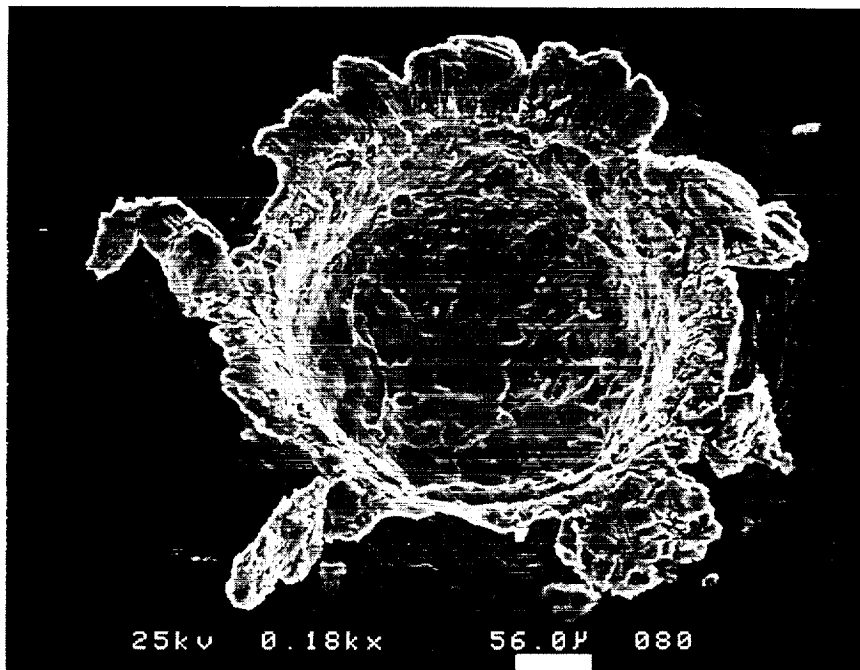
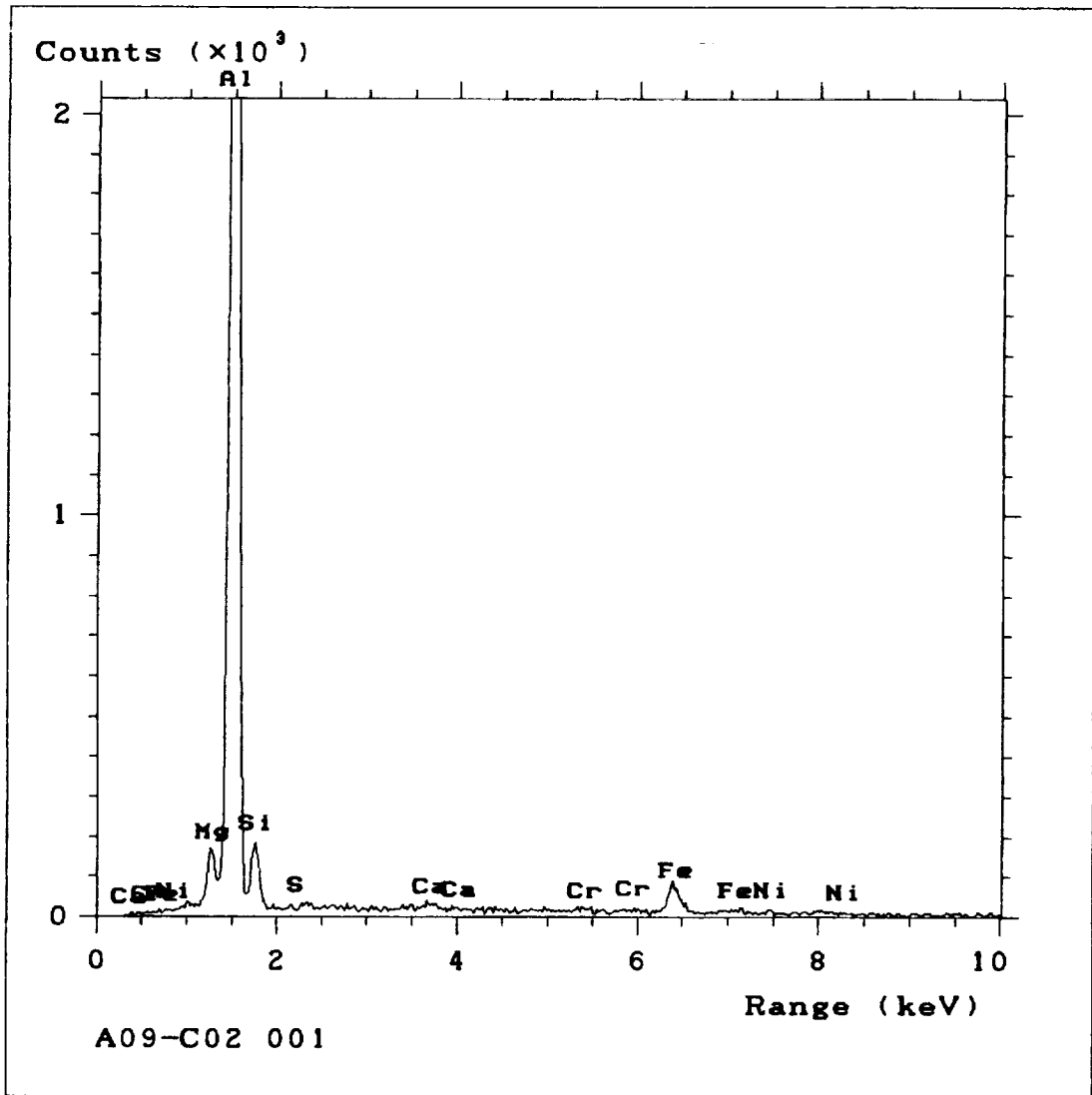


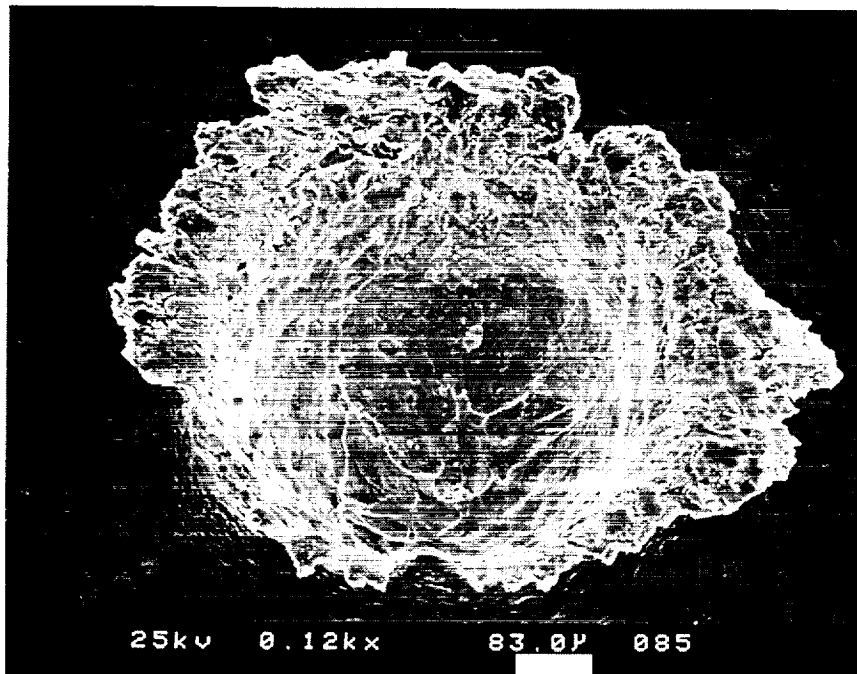
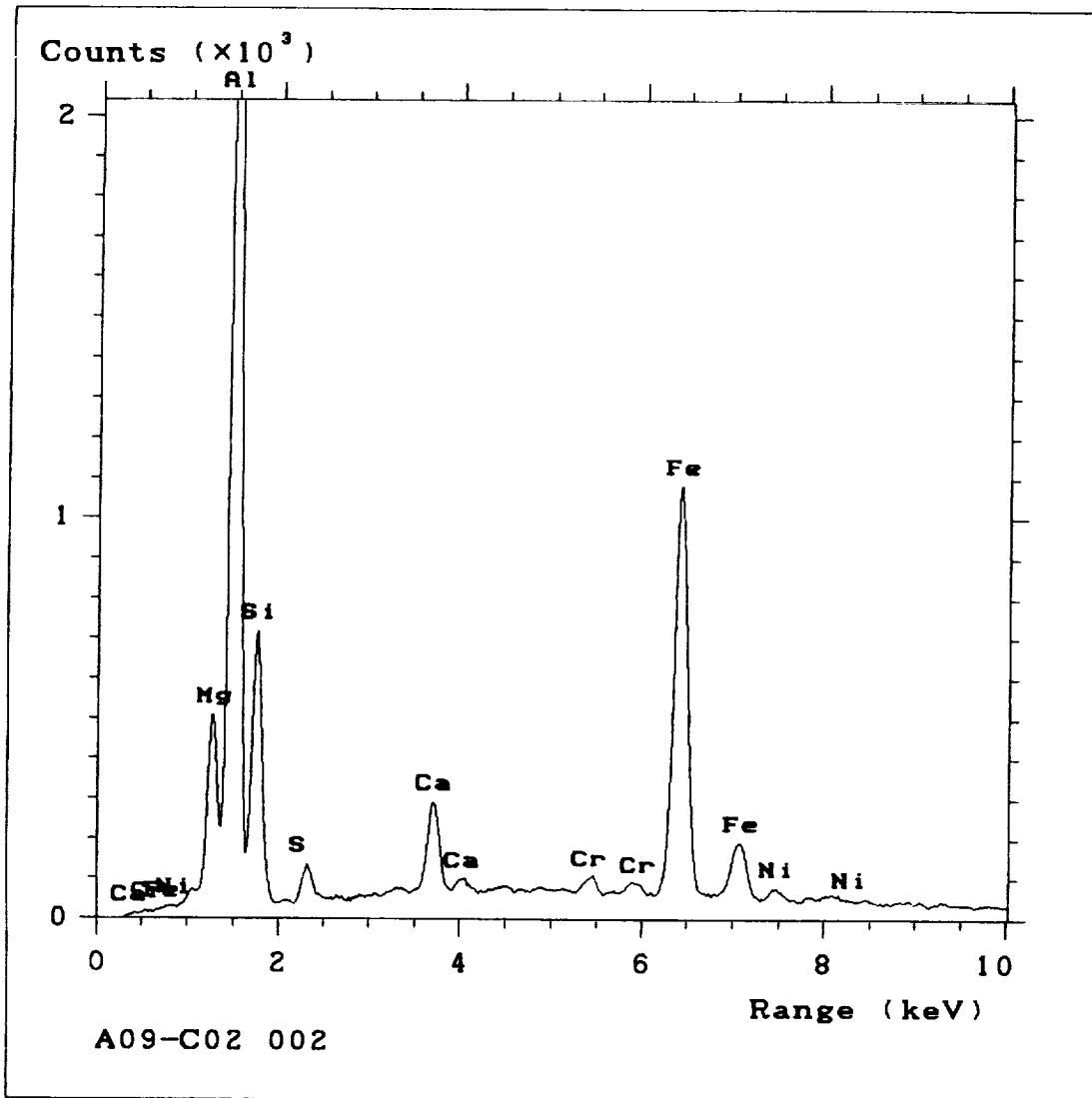


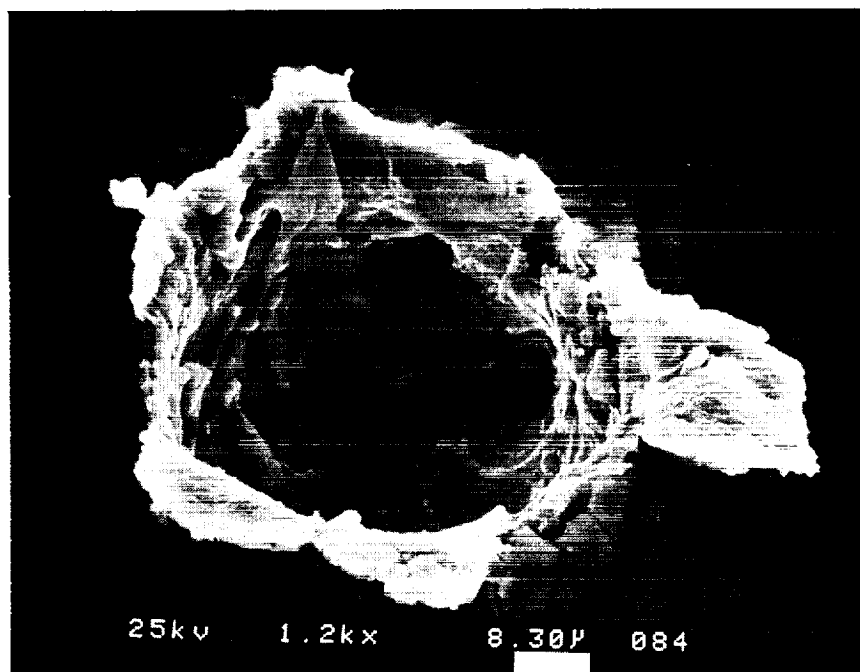
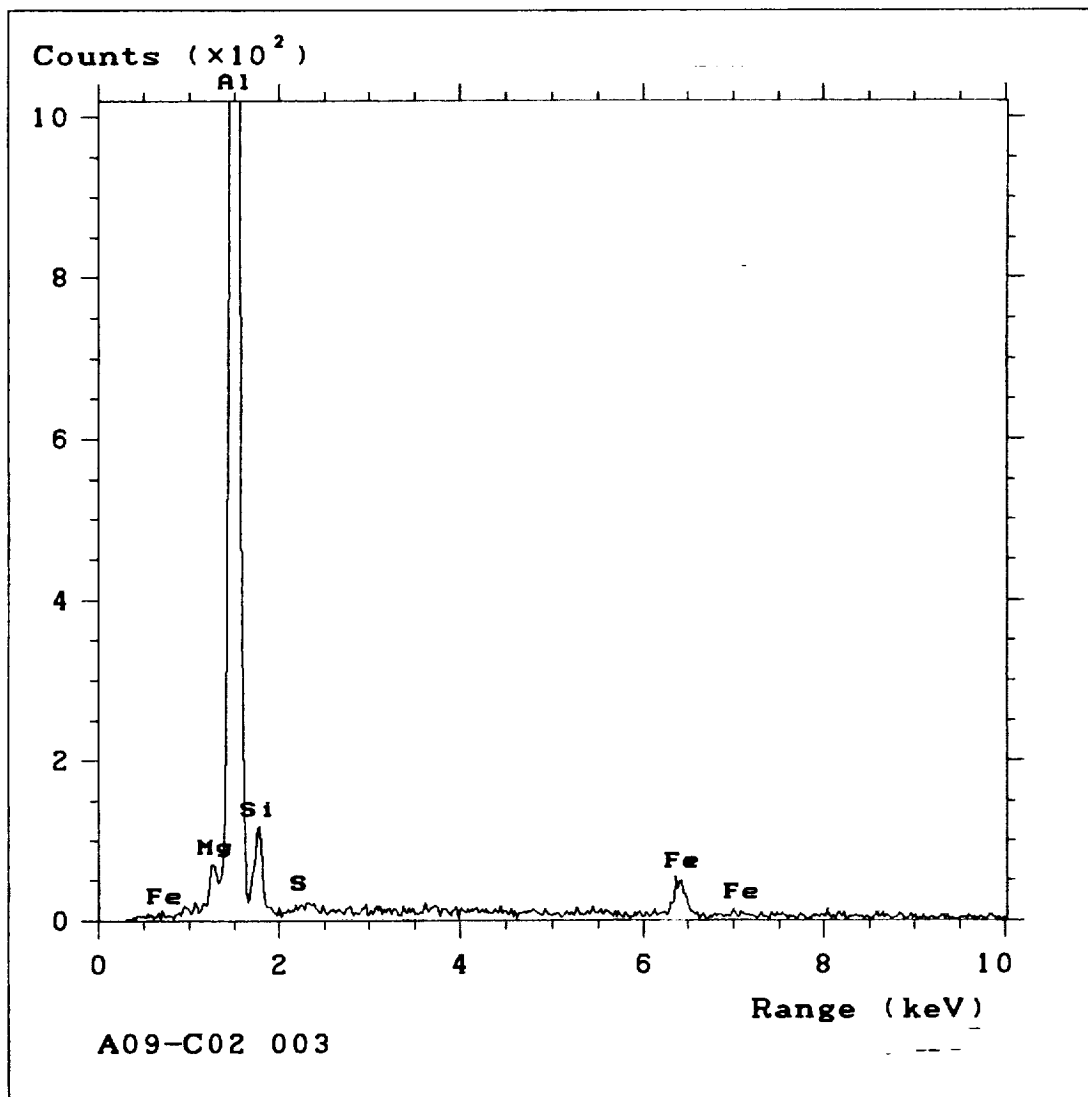
CLAMP NUMBER A09 CO2

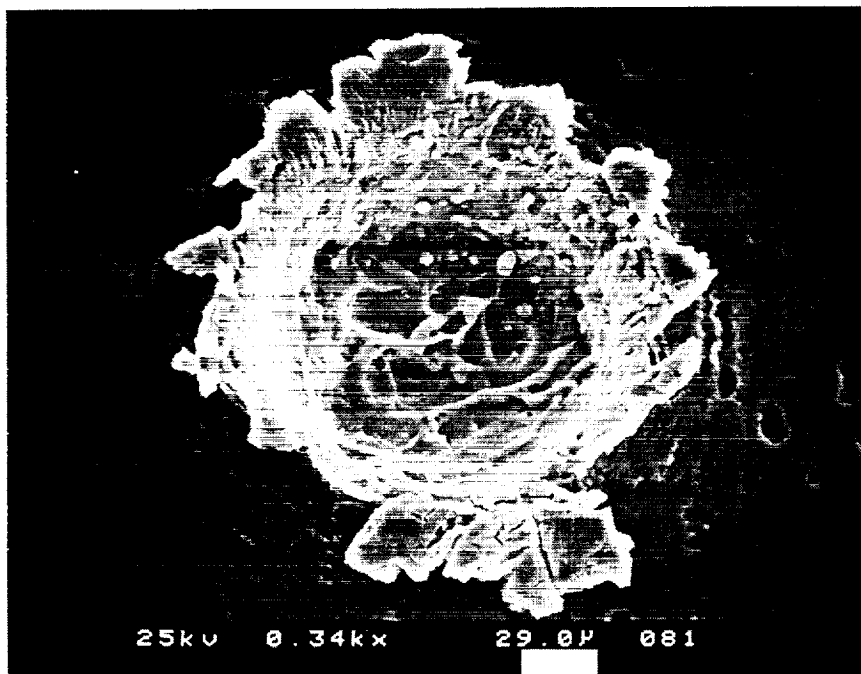
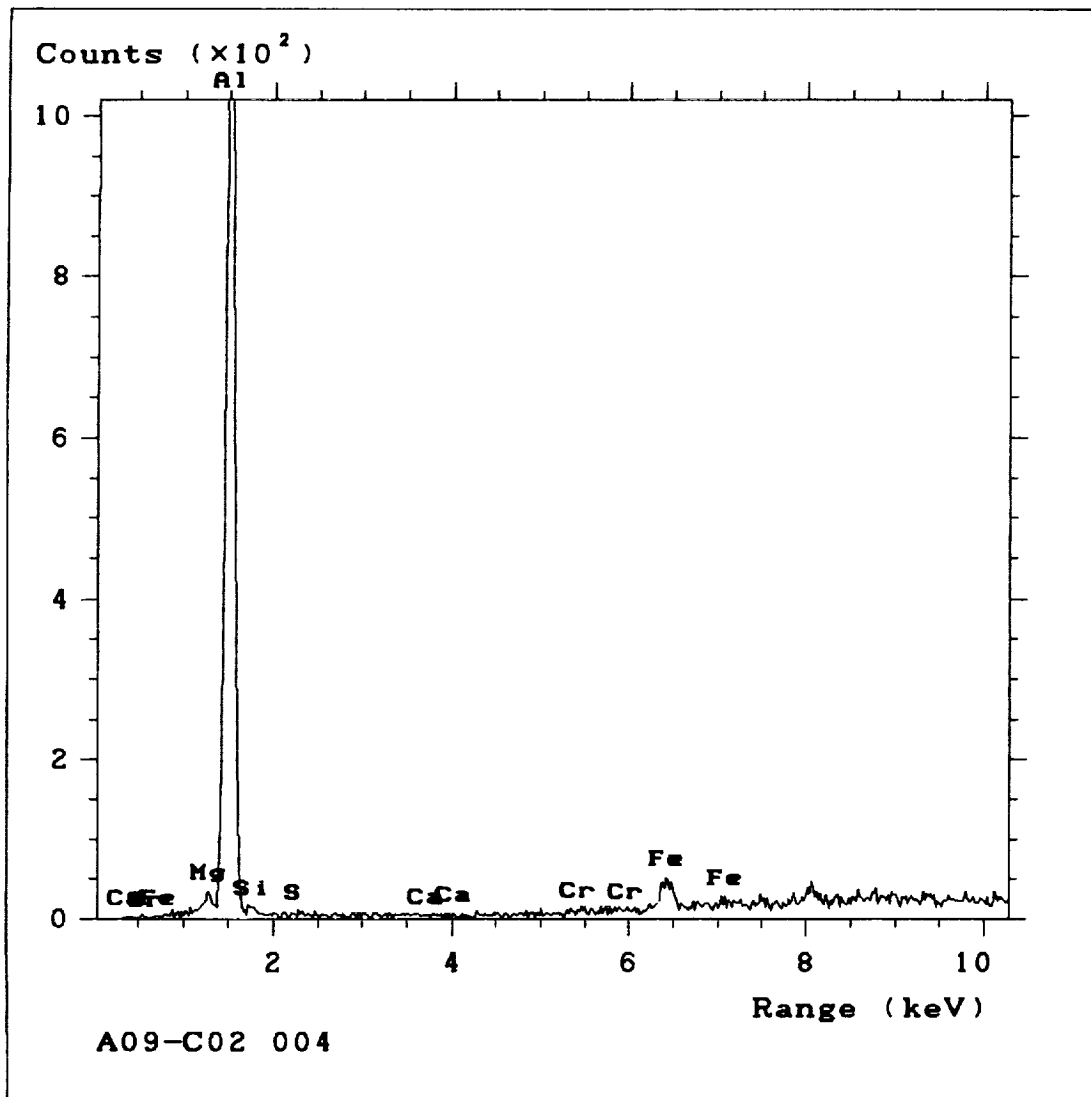
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	400	Trace
002	700	Micrometeoritic
003	60	Trace
004	160	Unknown
005	180	Unknown
006	100	Unknown
007	150	Paint Patch

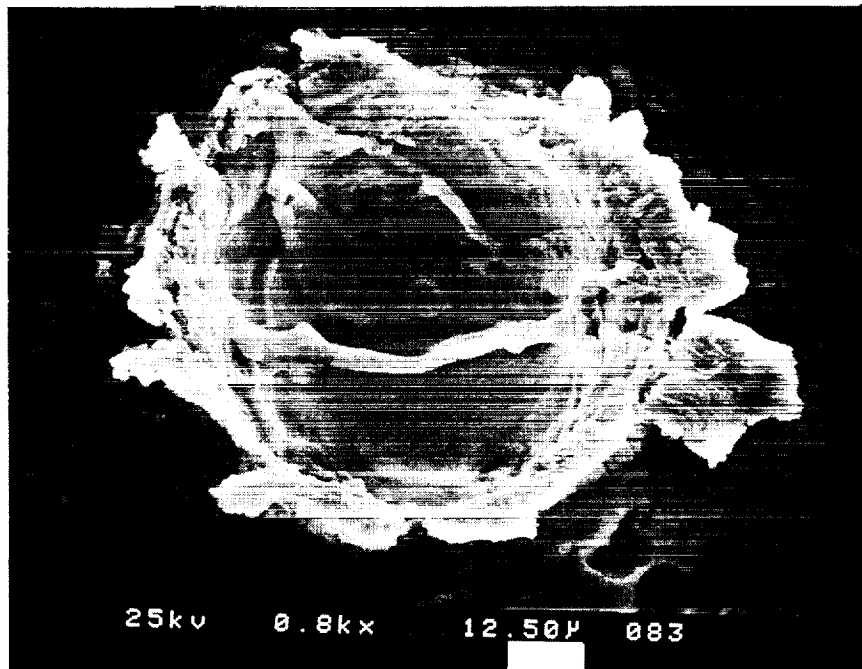
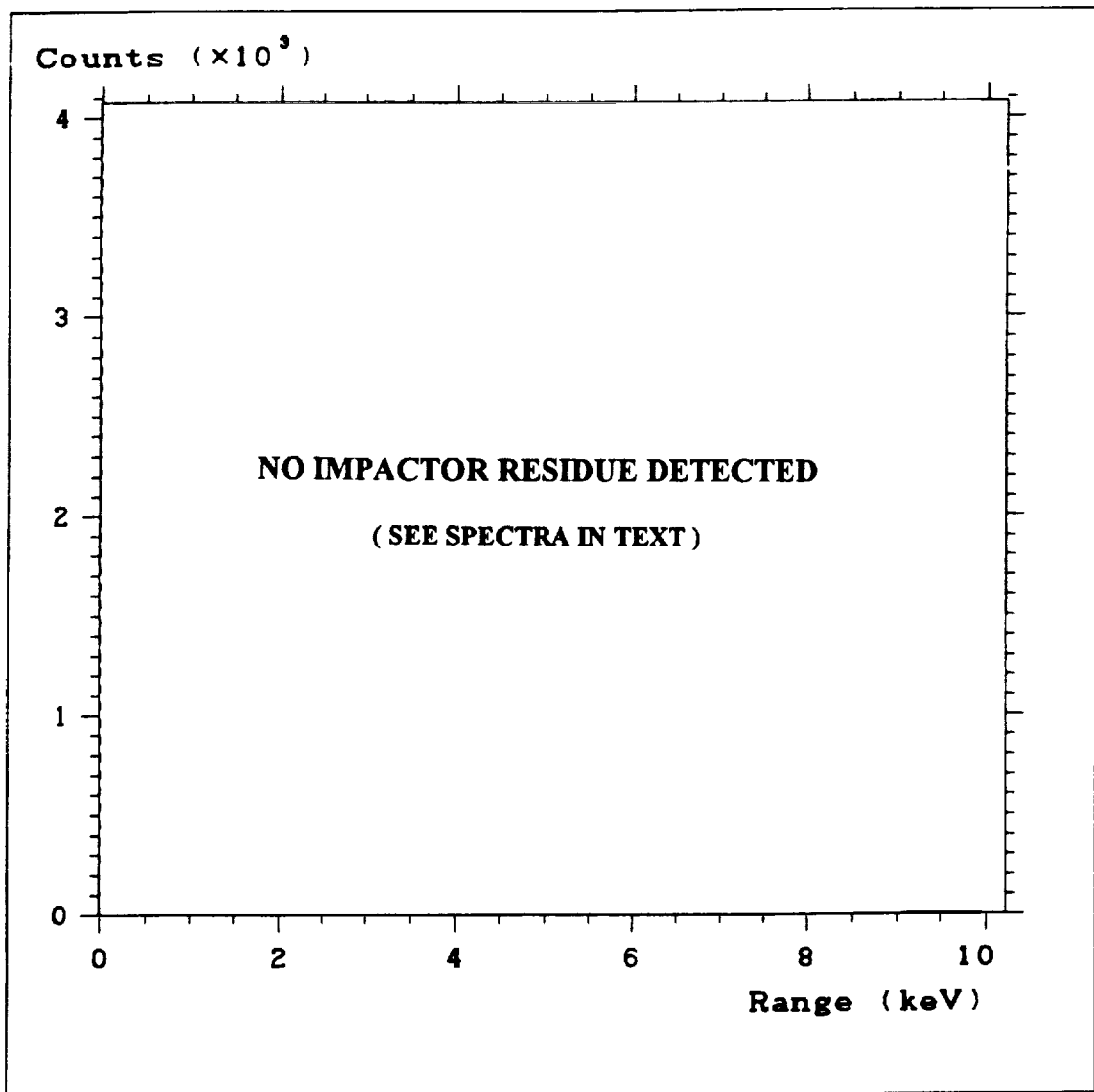


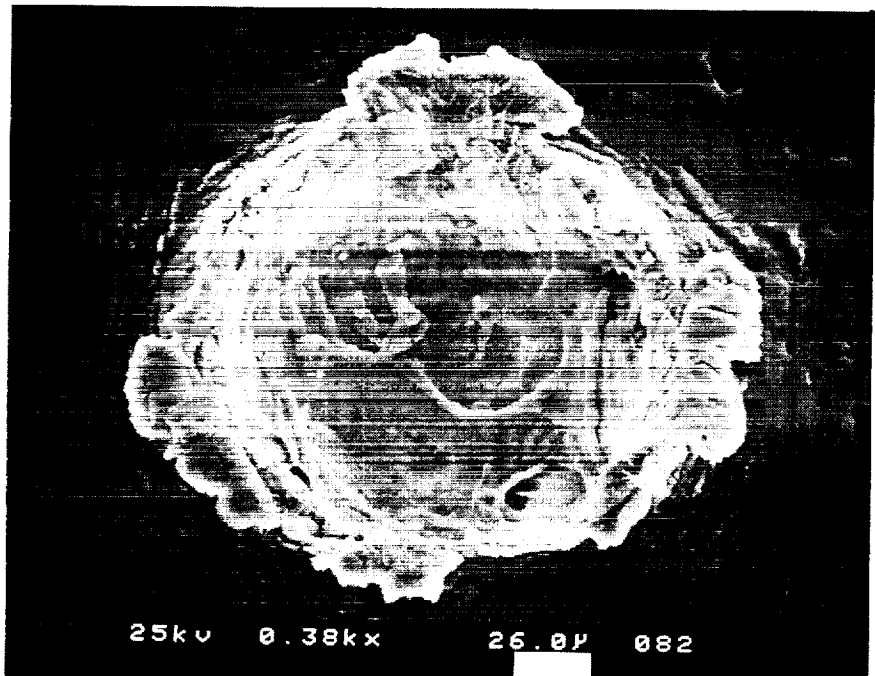
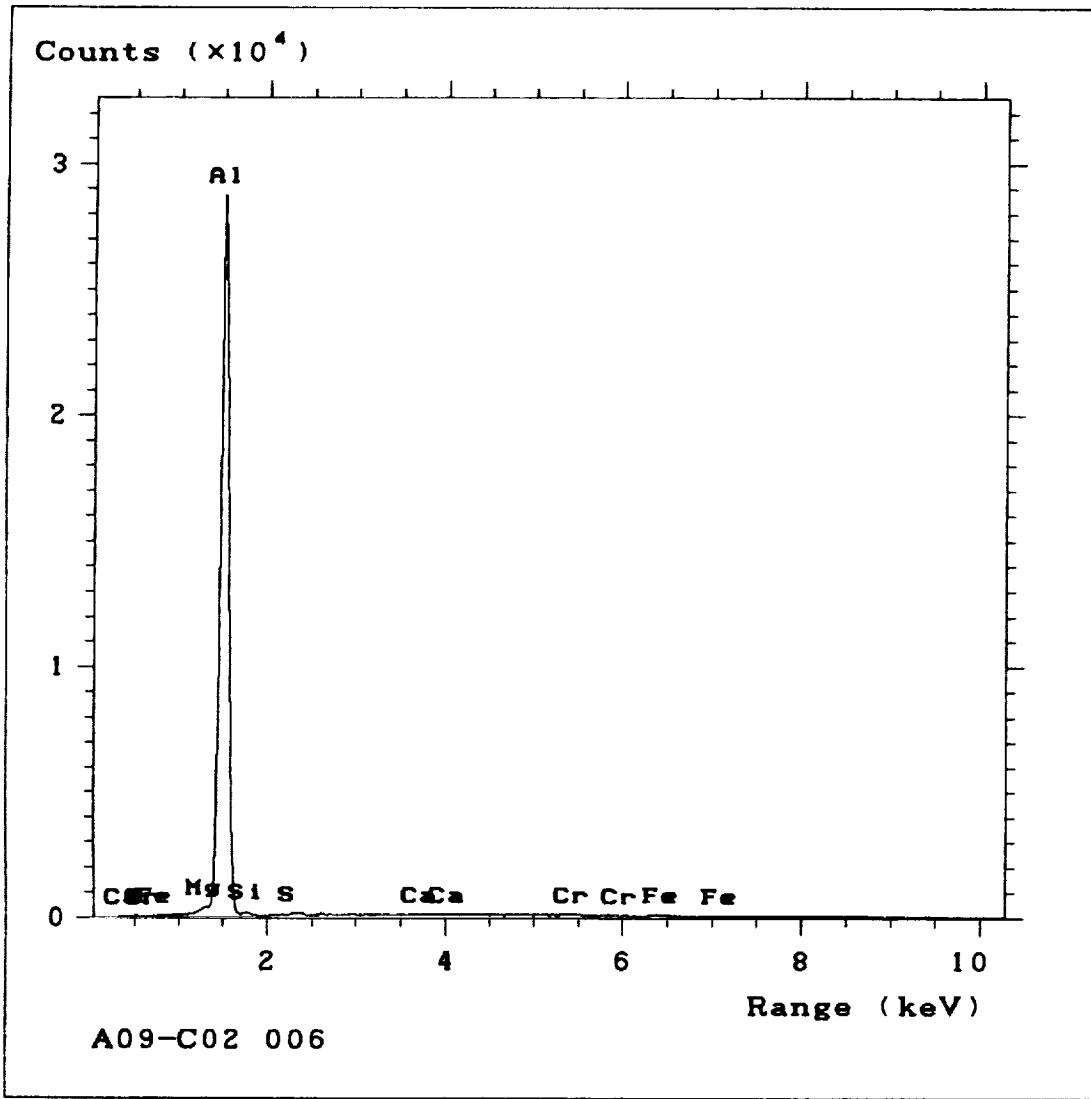






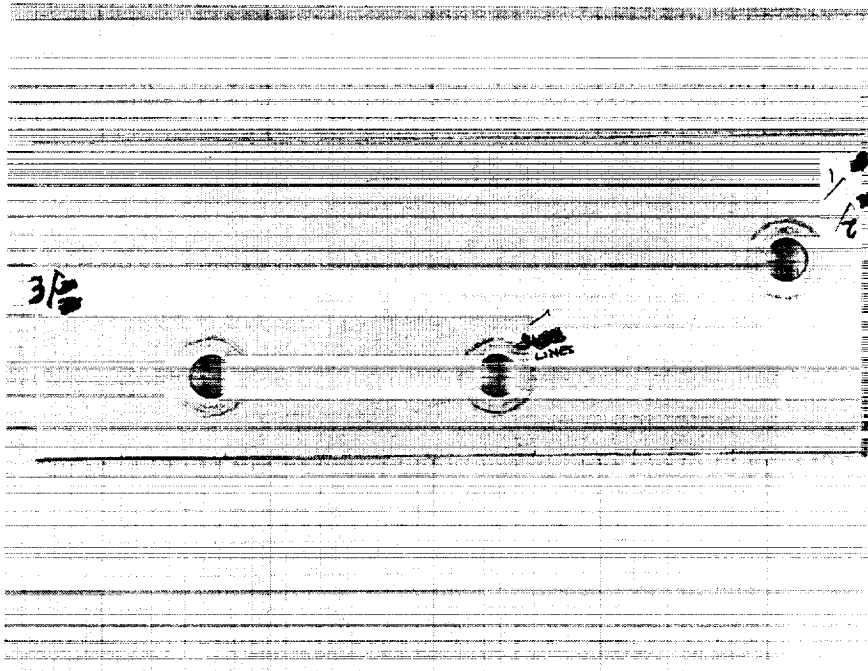


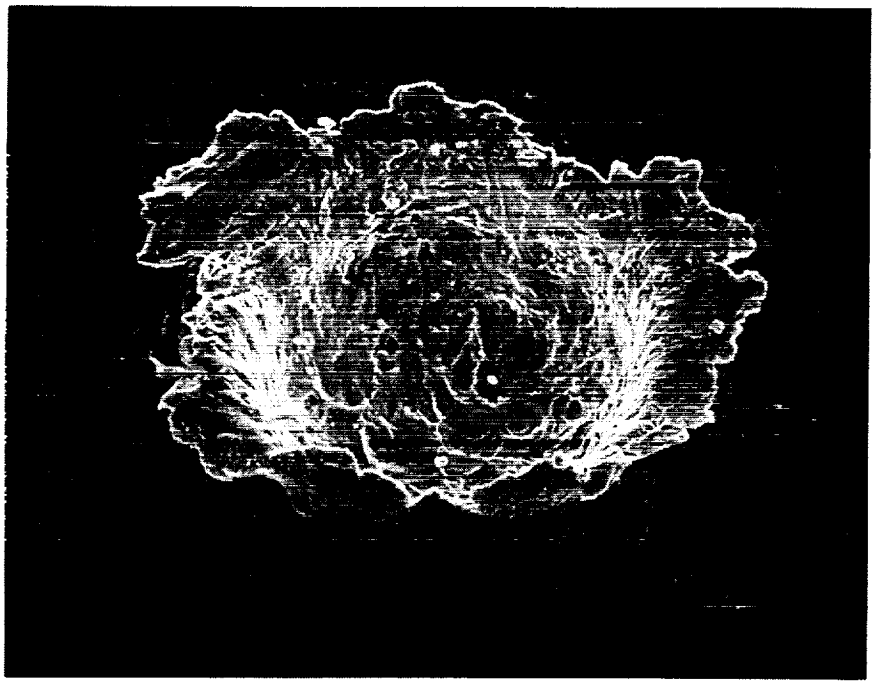
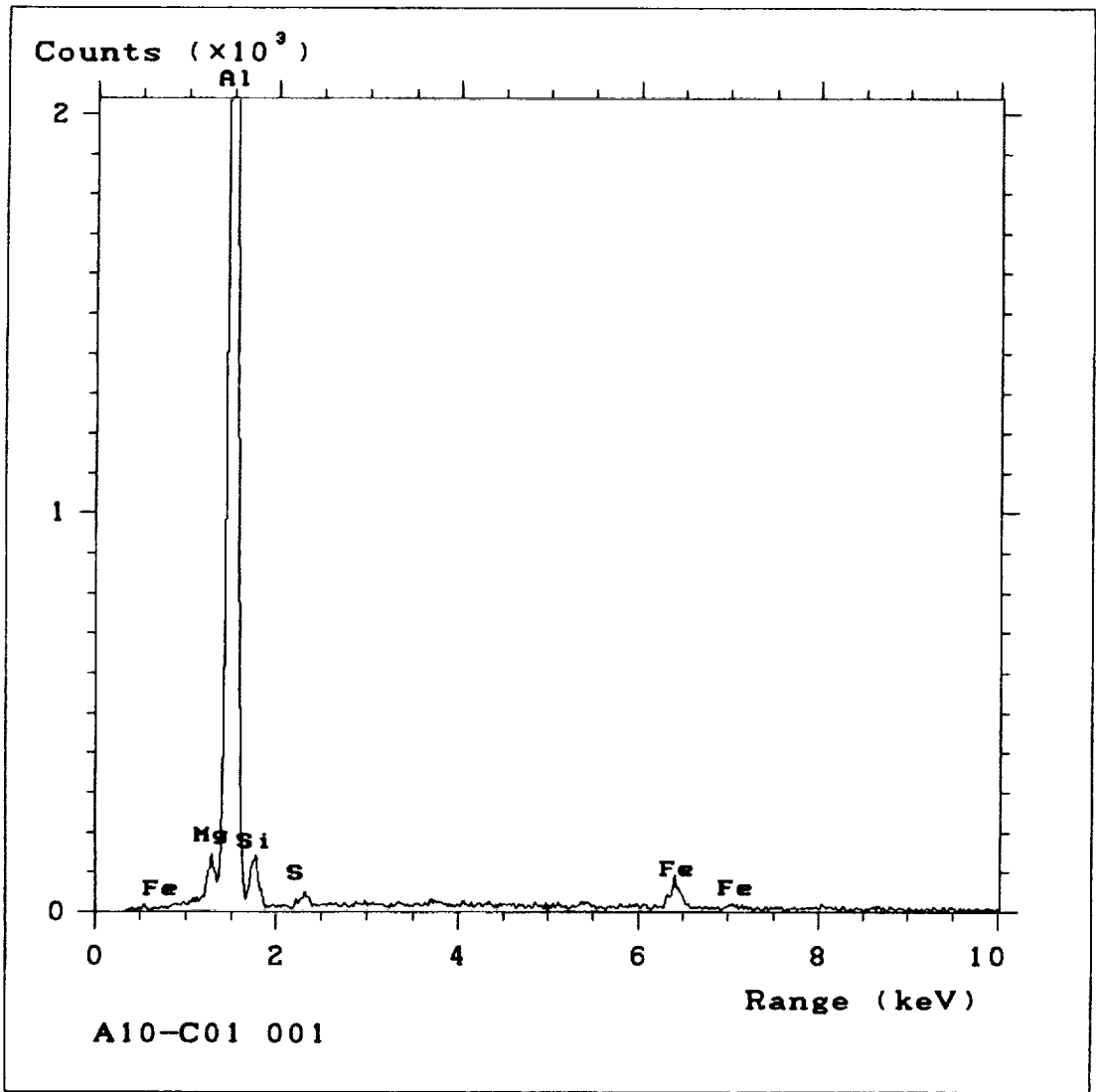


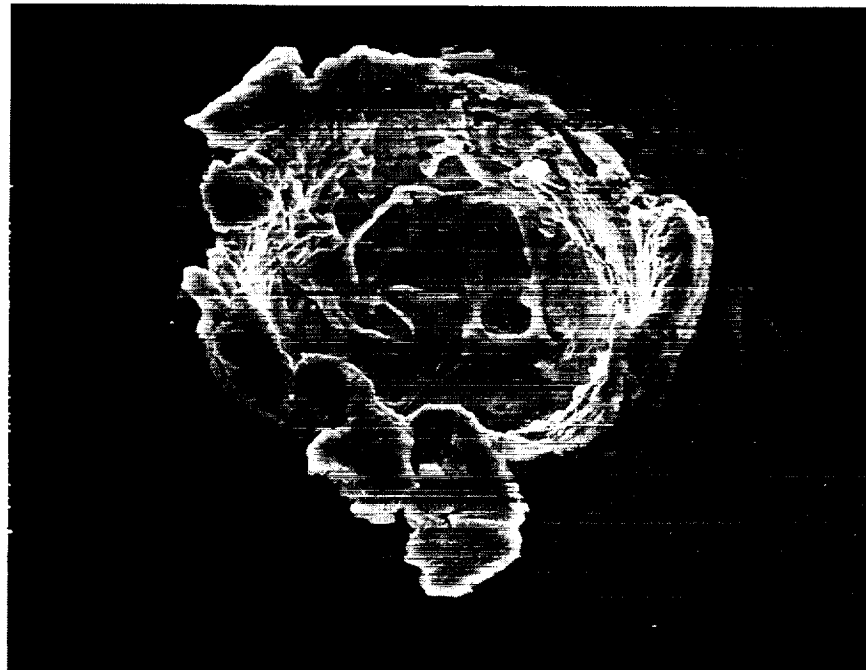
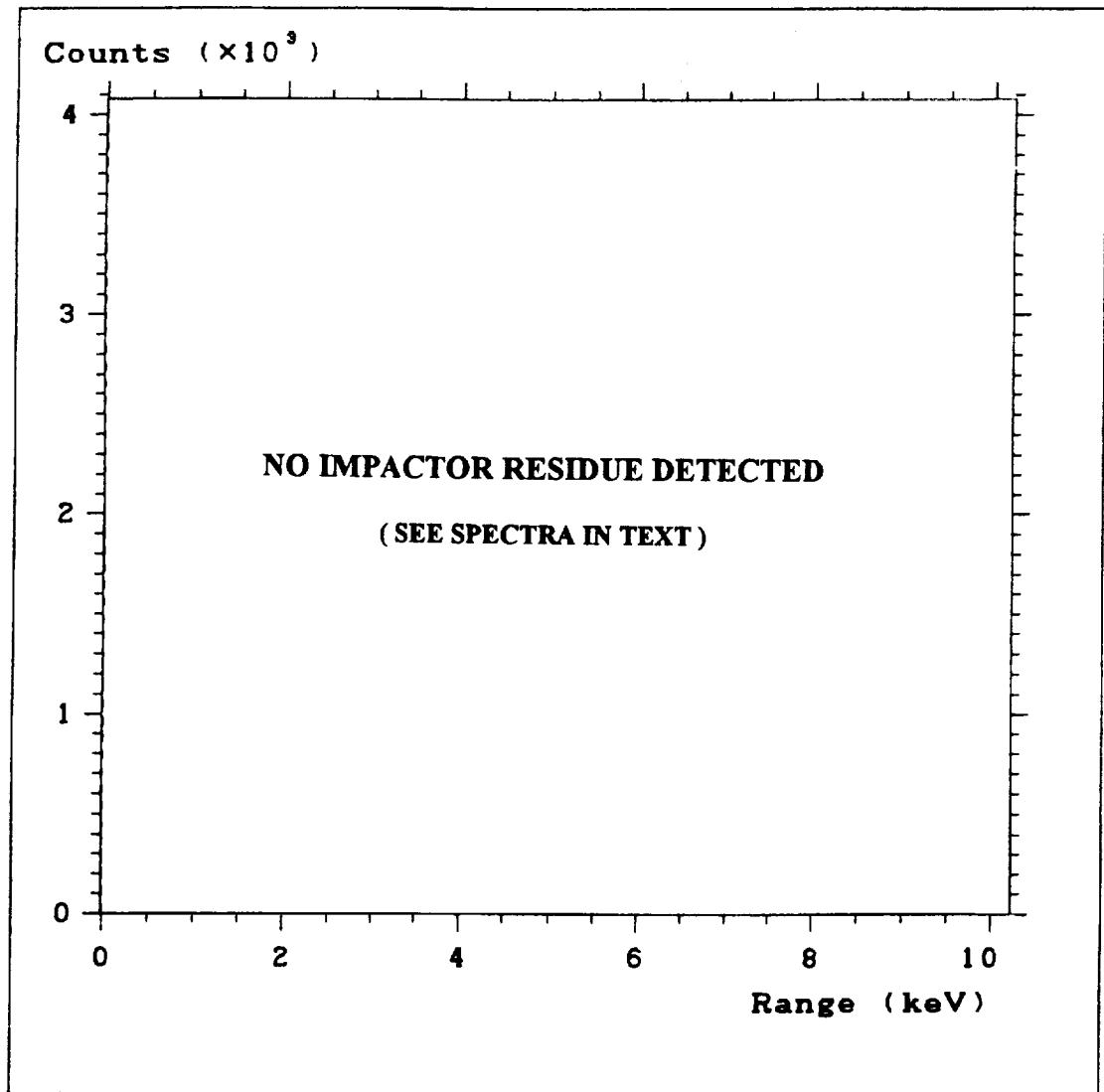


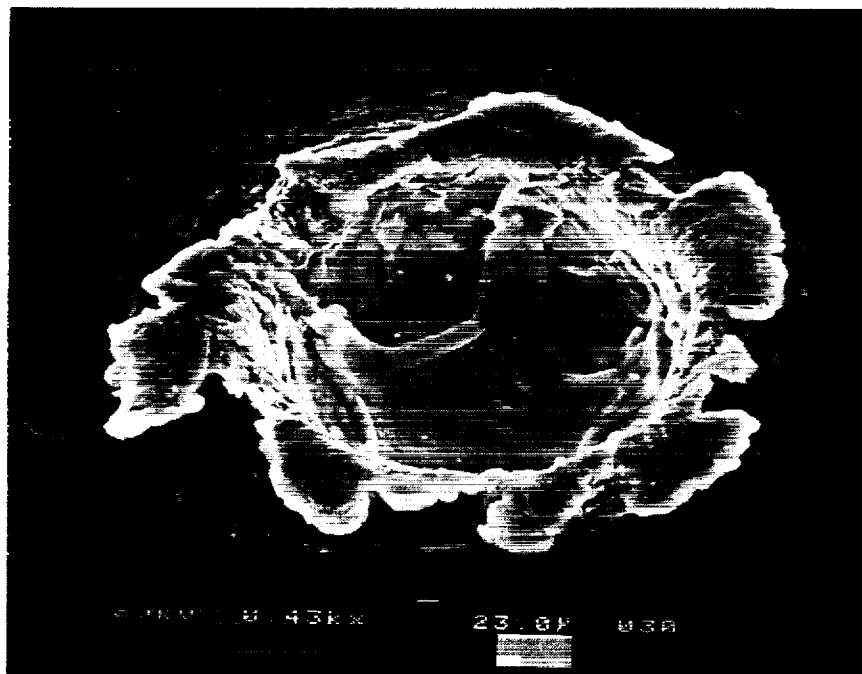
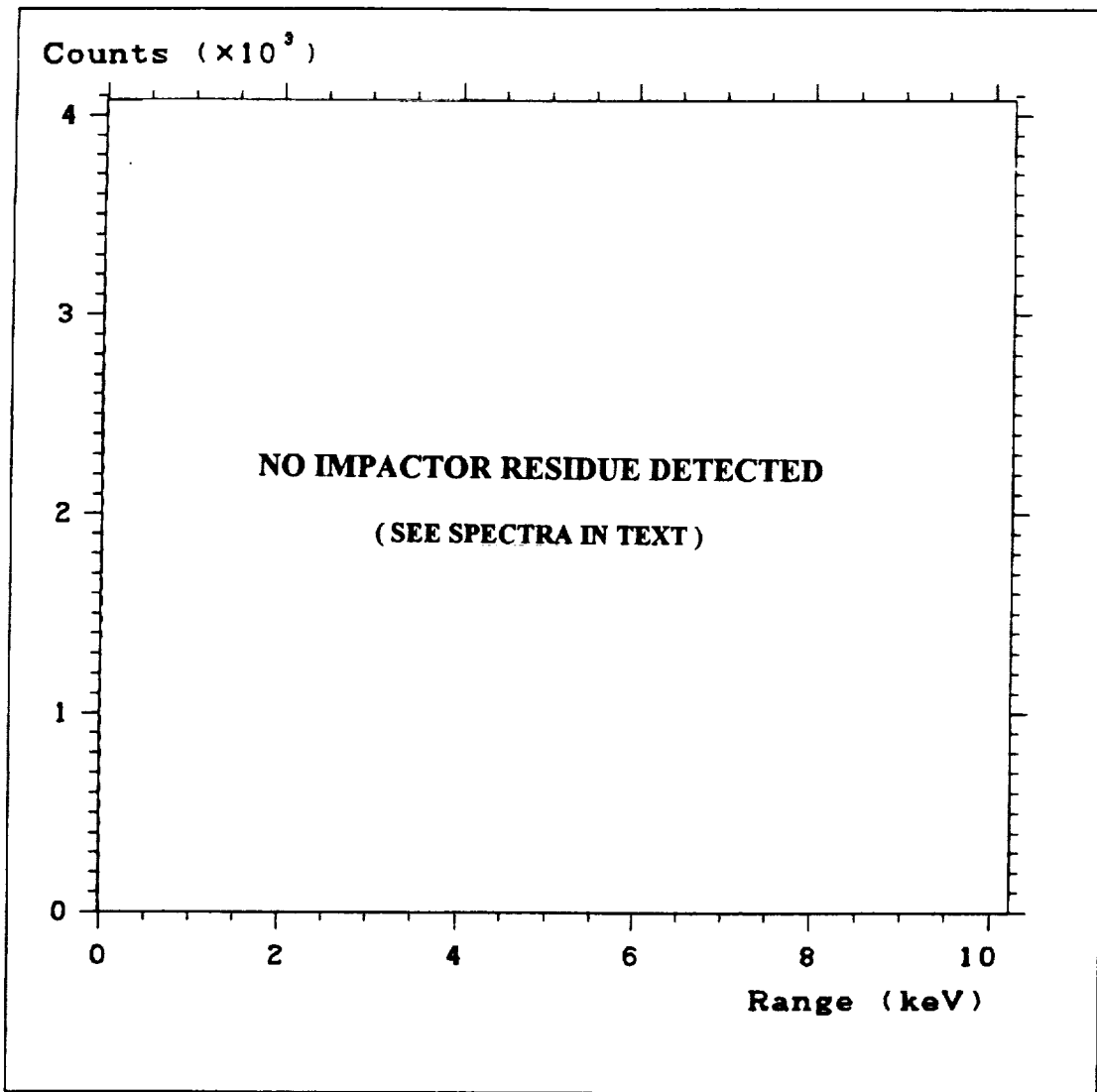
CLAMP NUMBER A10 CO1

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	250	Trace
002	100	Unknown
003	120	Unknown



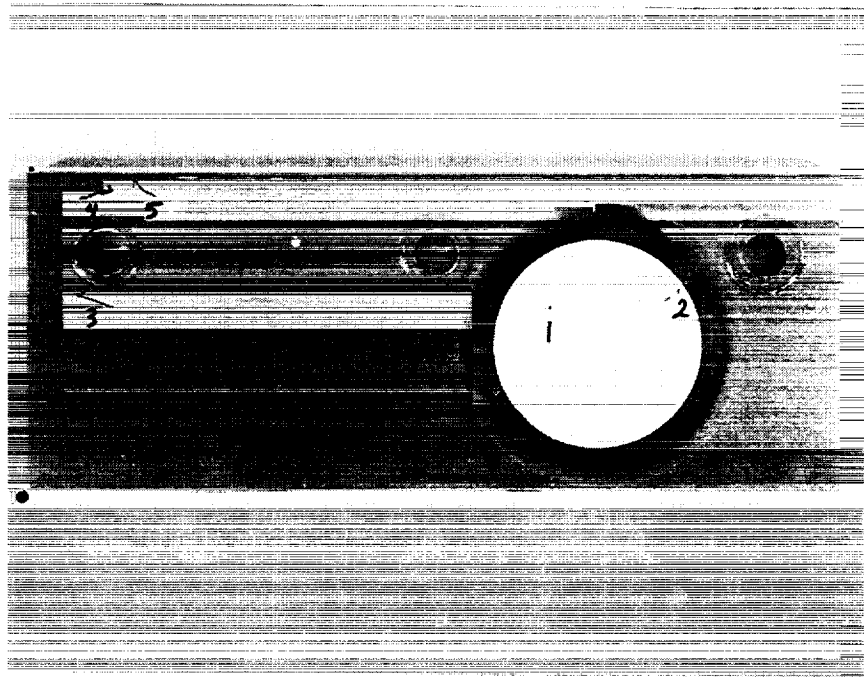


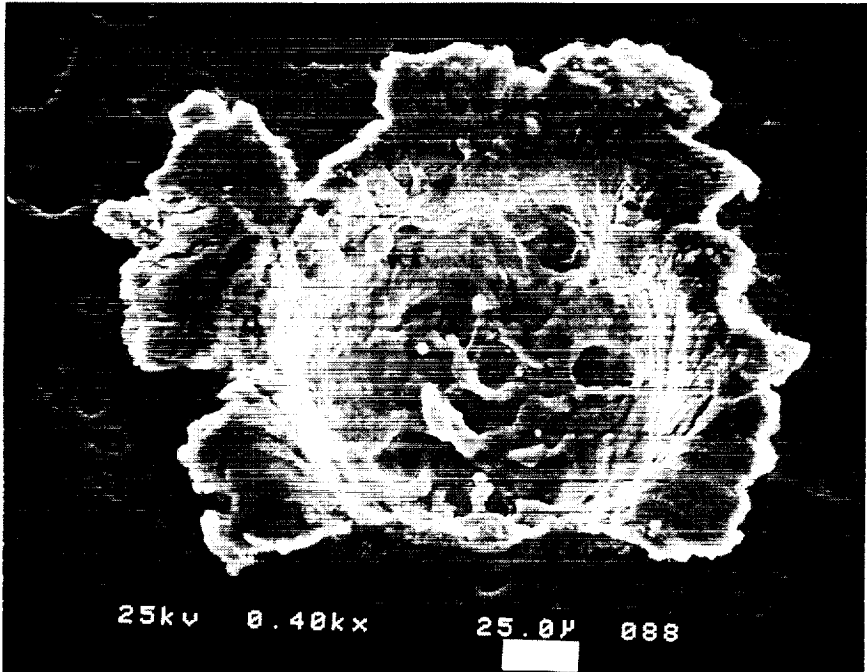
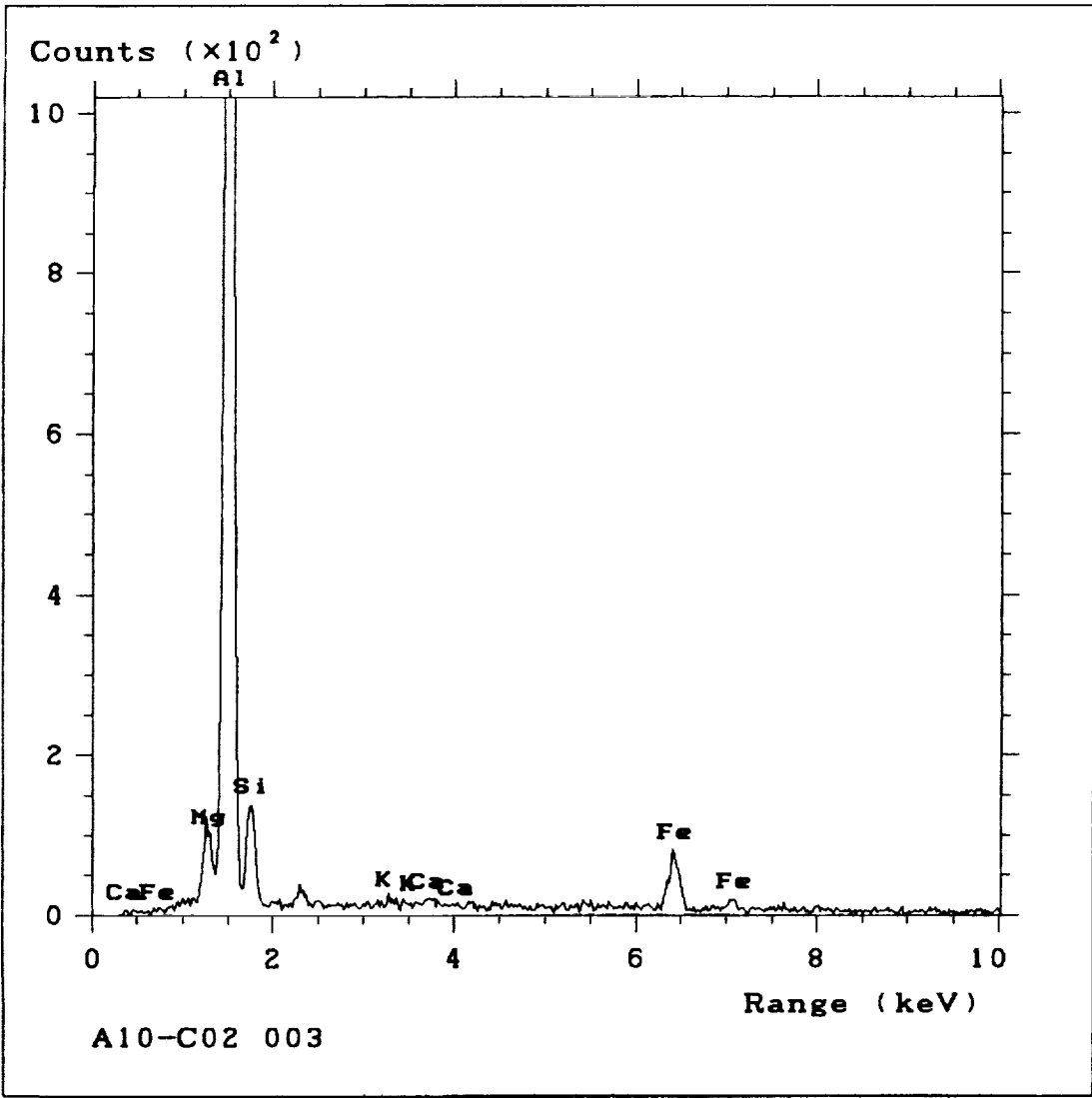


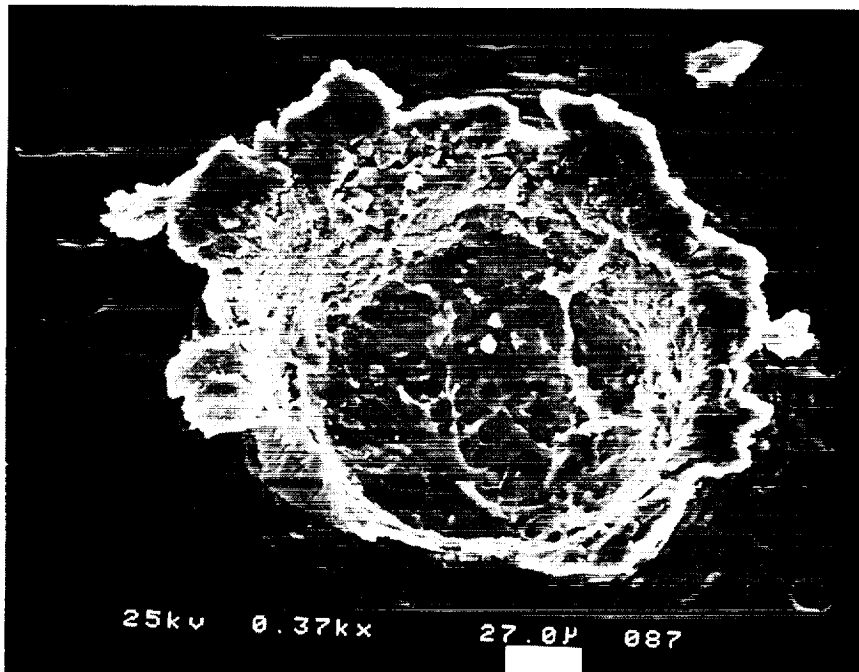
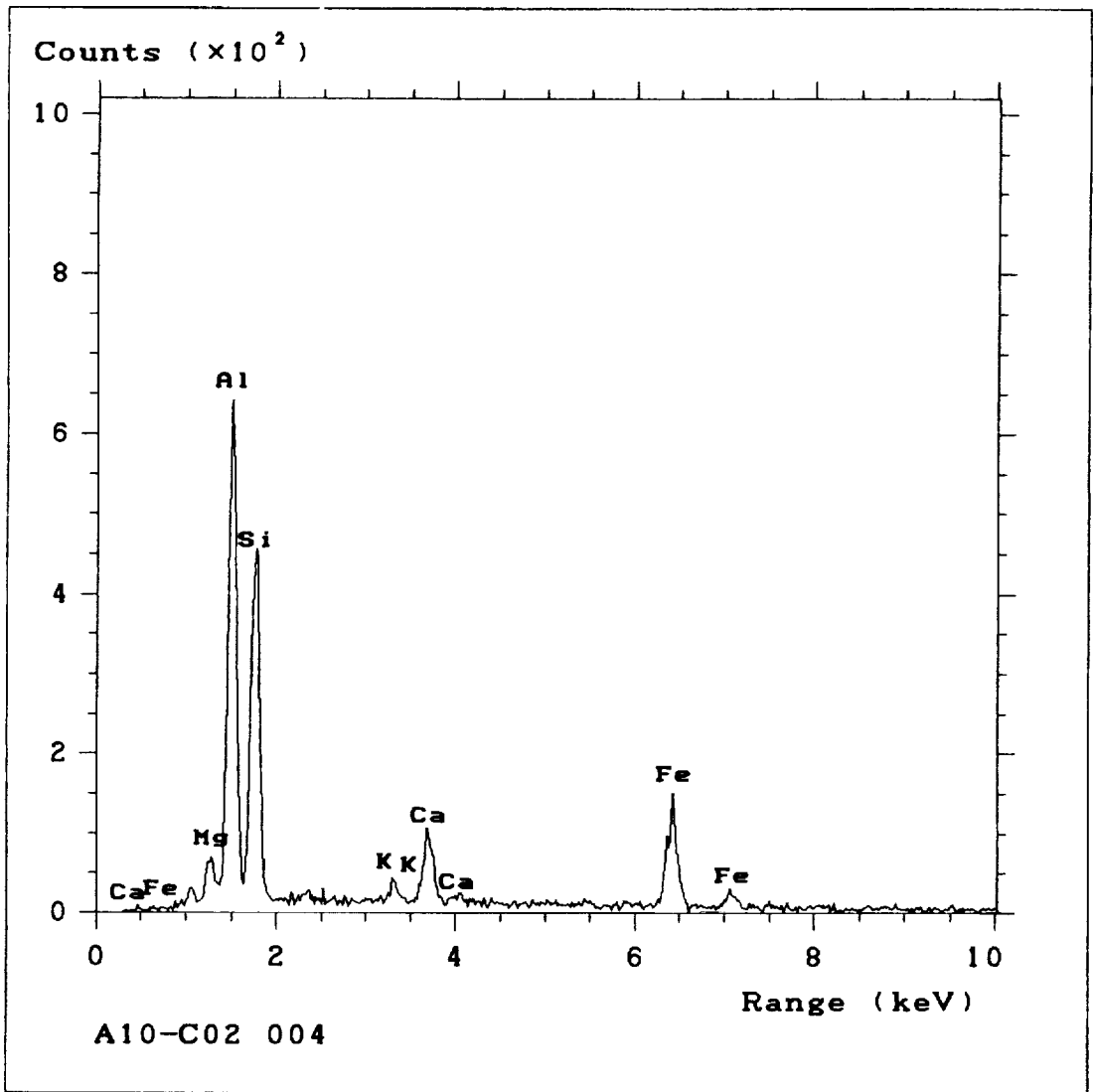


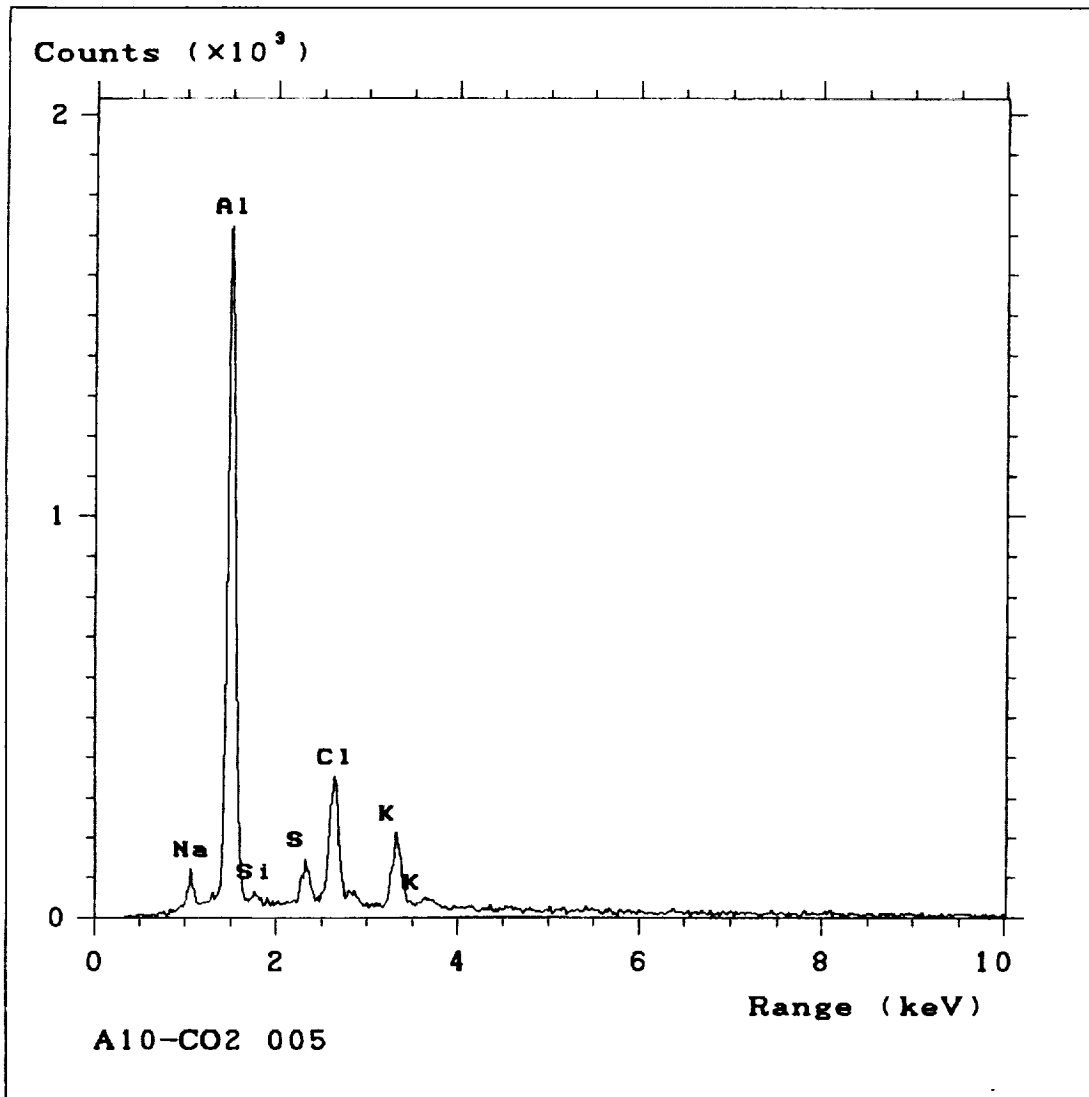
CLAMP NUMBER A10 CO2

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	400	Paint Patch
002	230	Paint Patch
003	150	Trace
004	180	Si, Mg, Fe
005	60	Contaminated



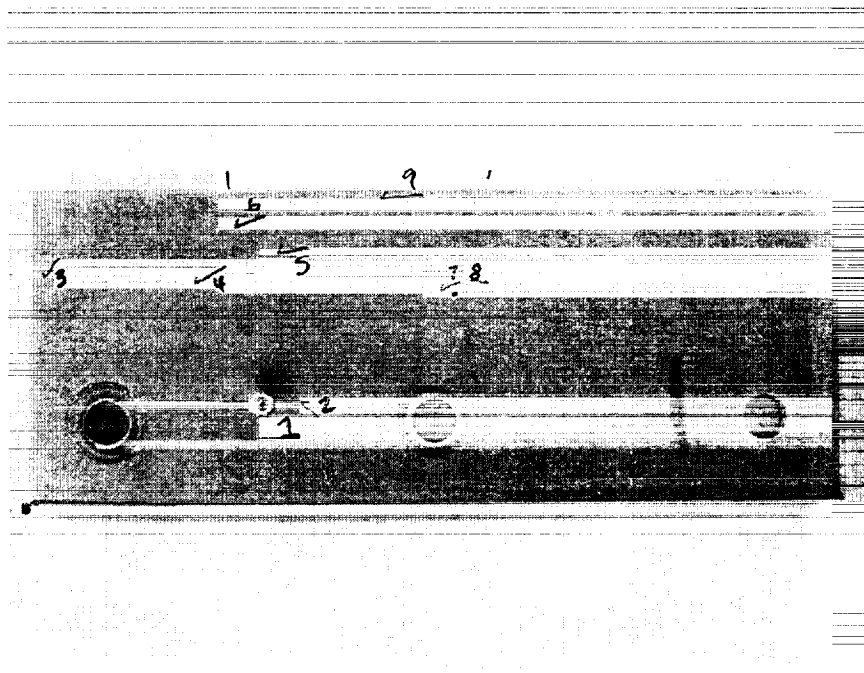


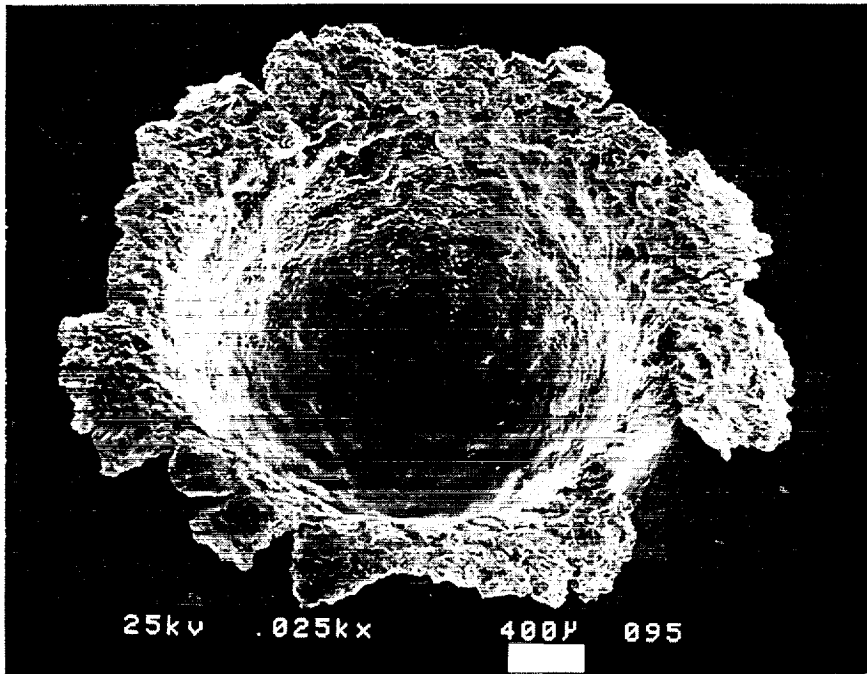
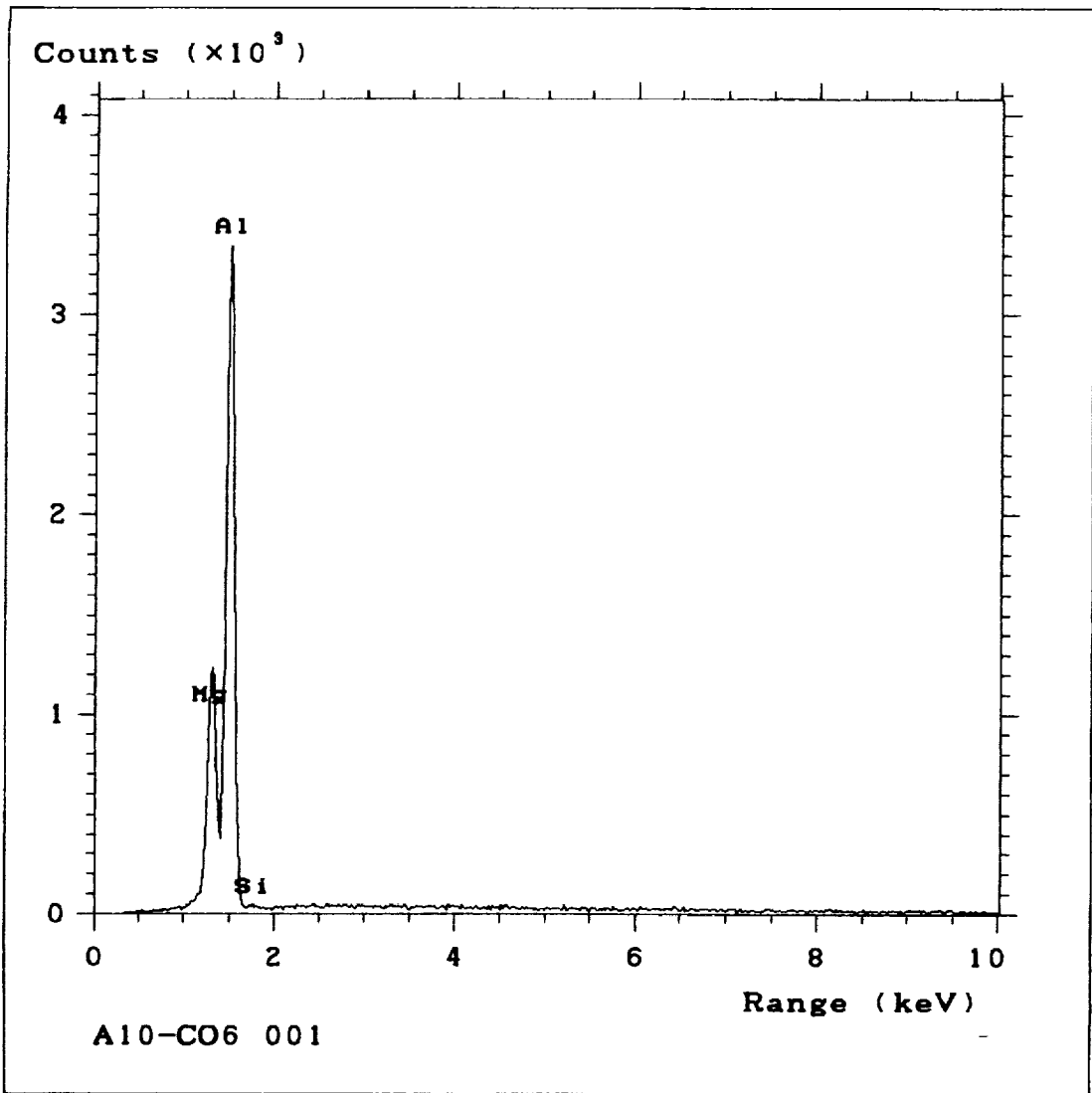


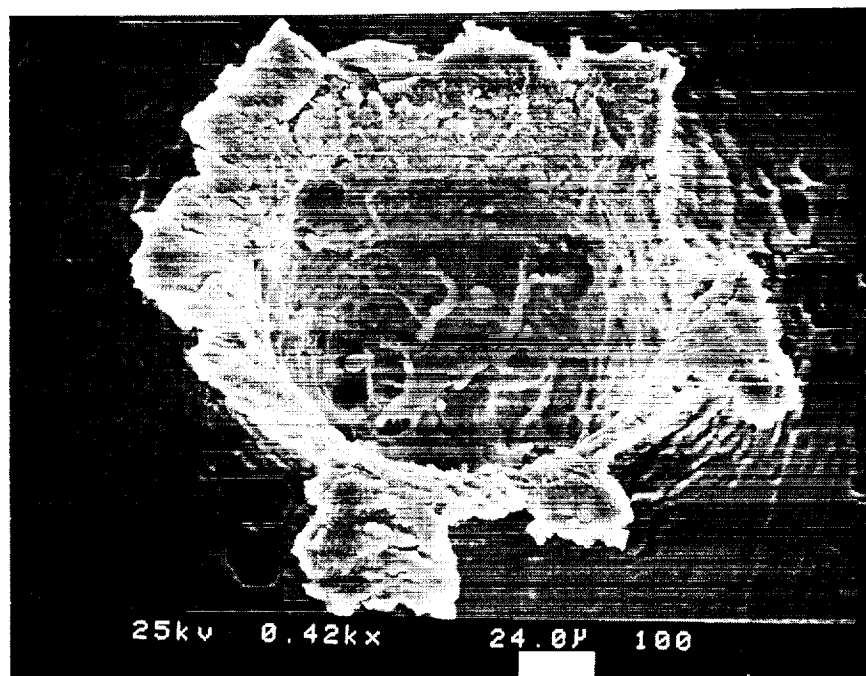
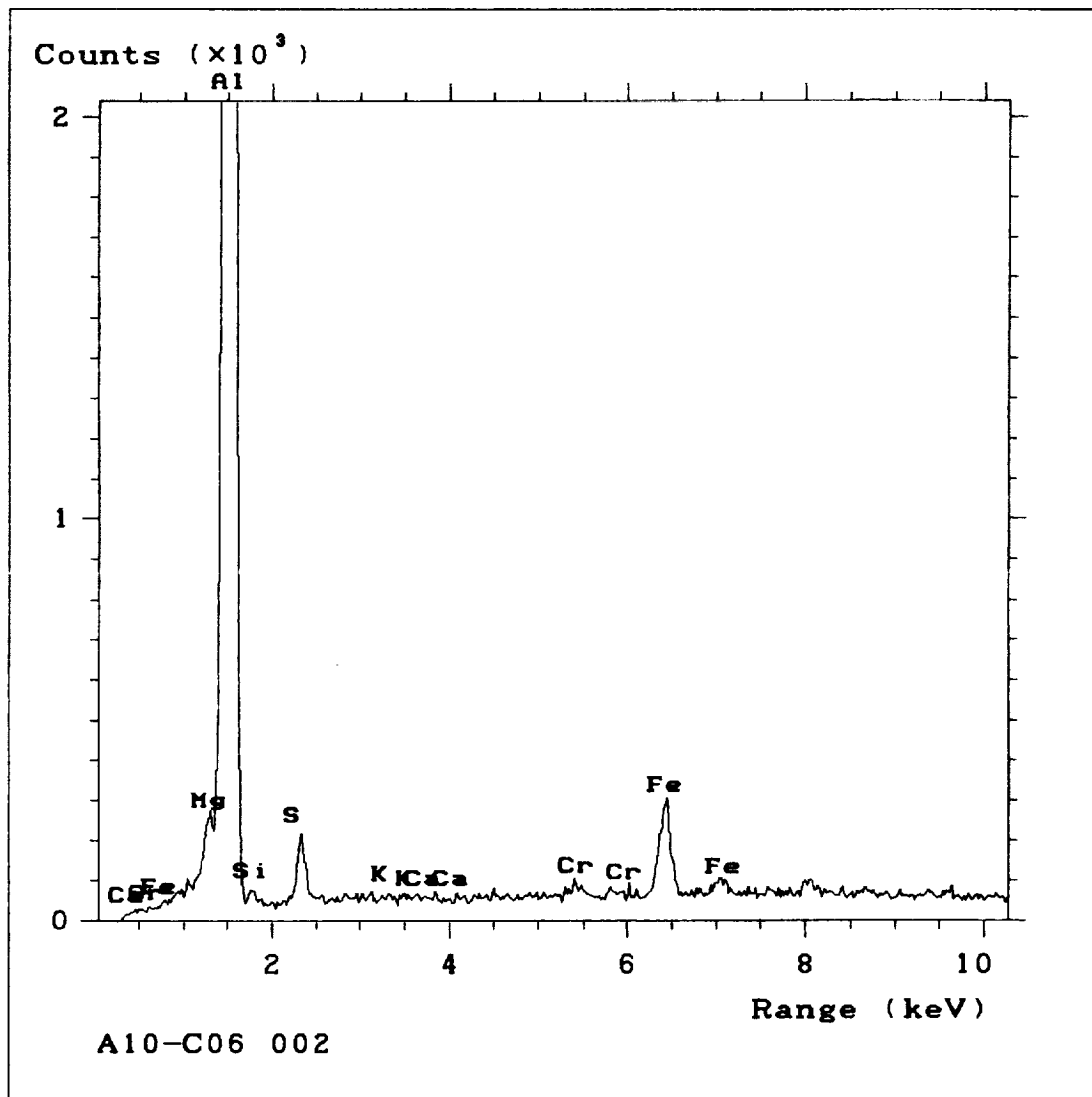


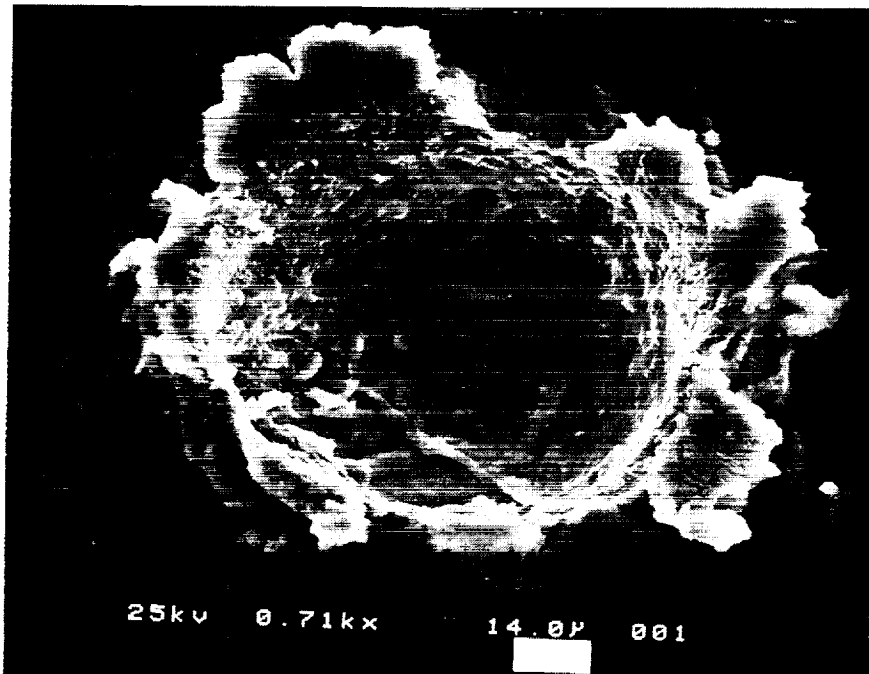
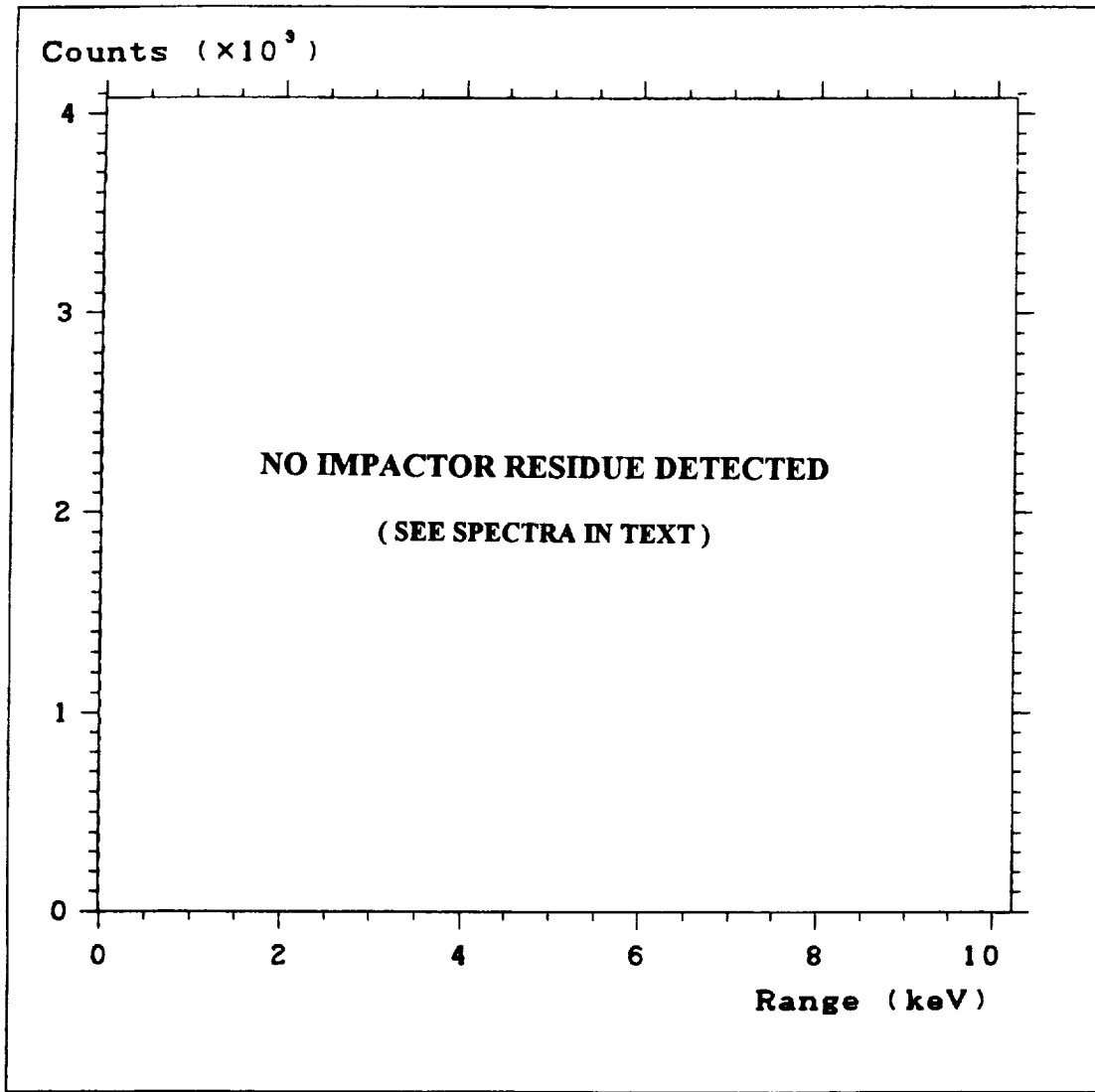
CLAMP NUMBER A10 CO6

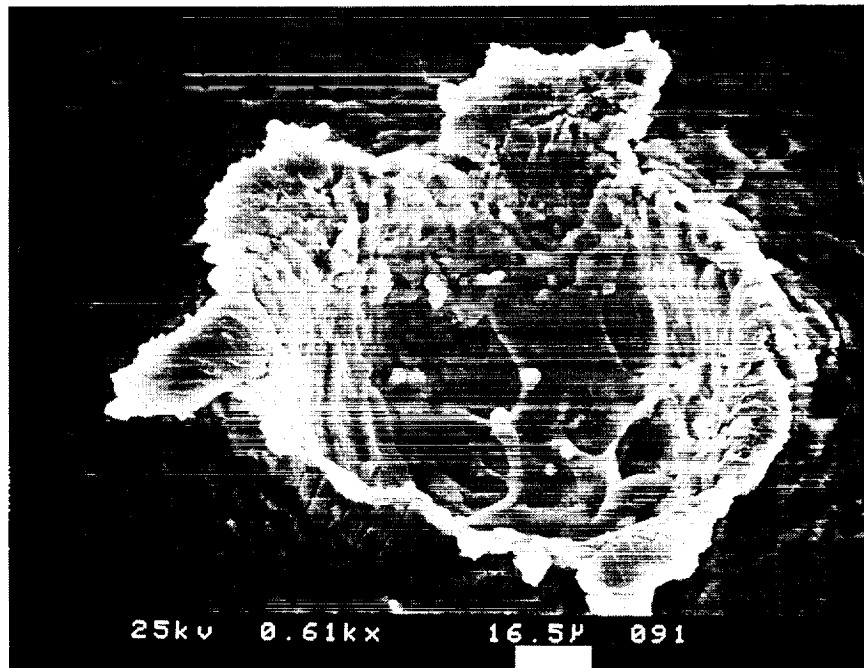
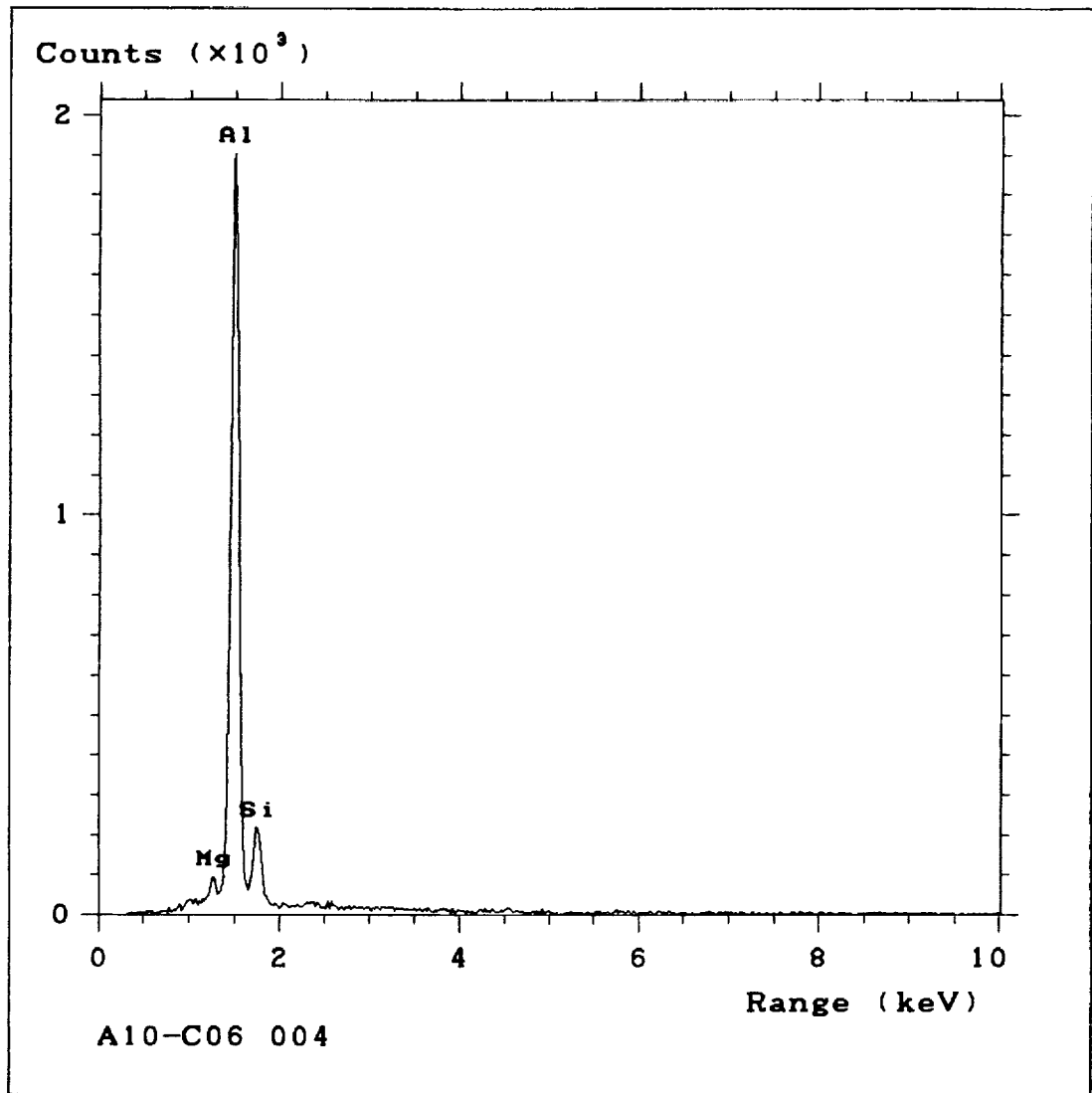
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	2800	Mg
002	200	Si, Mg, Fe
003	100	Unknown
004	120	Trace
005	150	Unknown
006	170	Unknown
007	80	Unknown
008	470	Unknown
009	200	Unknown

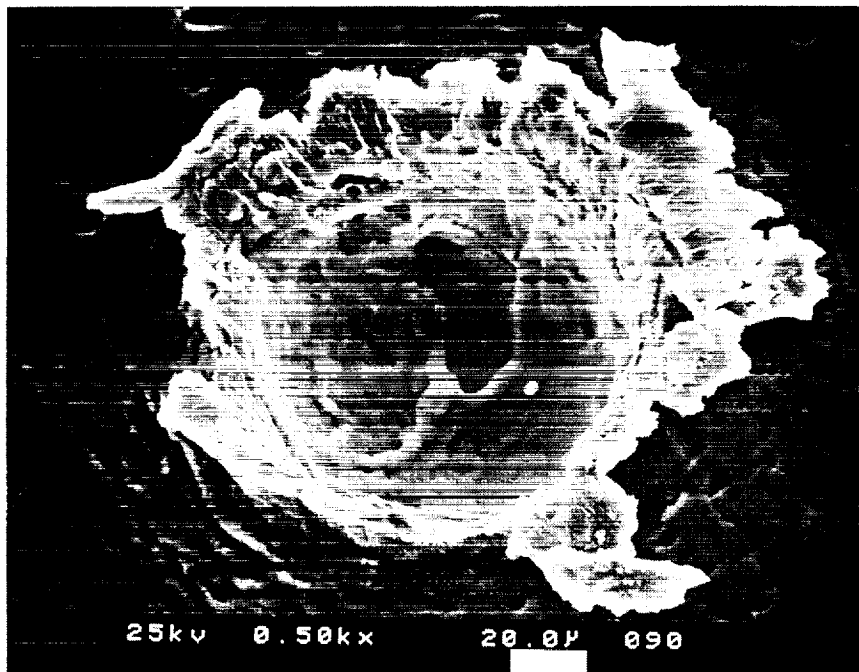
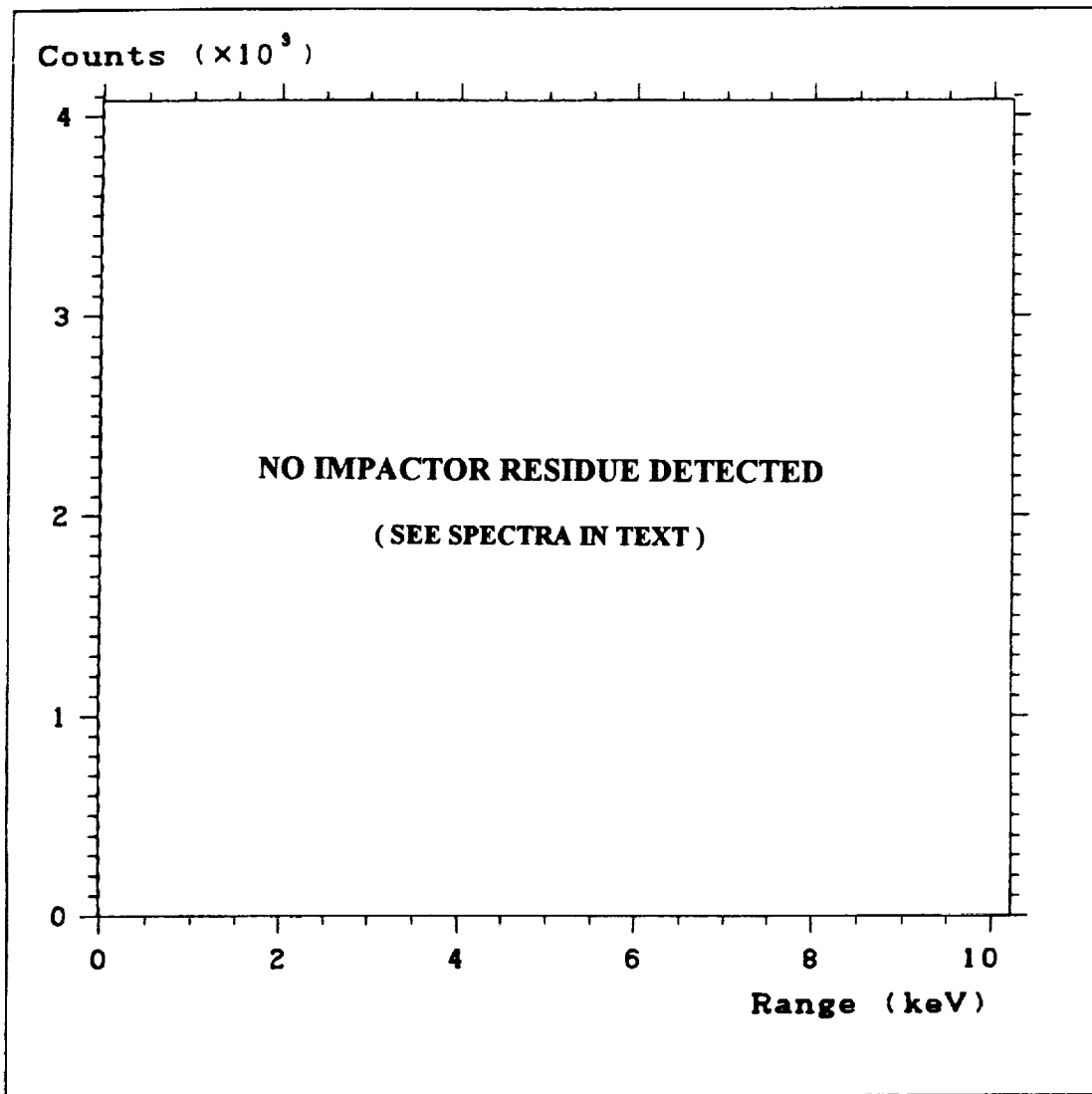


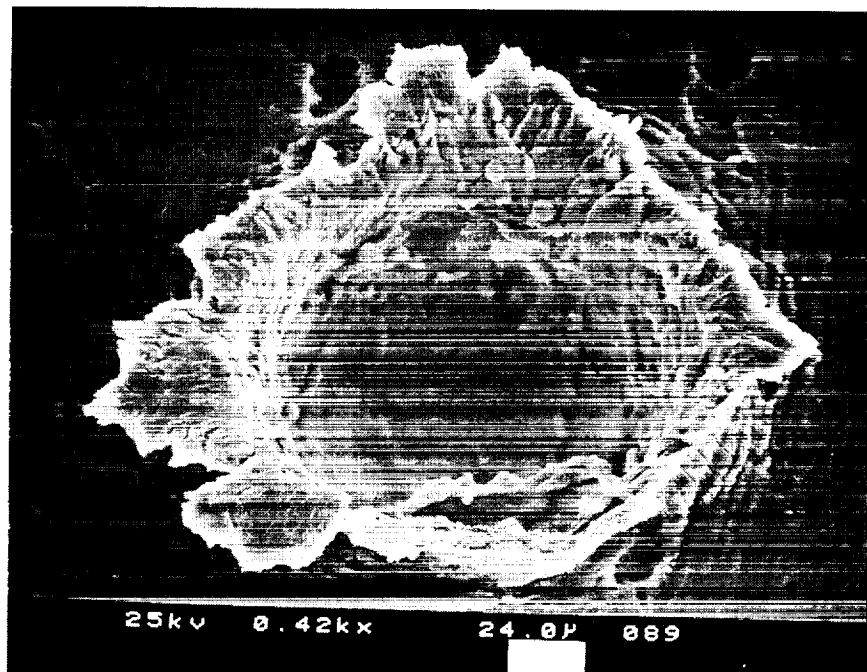
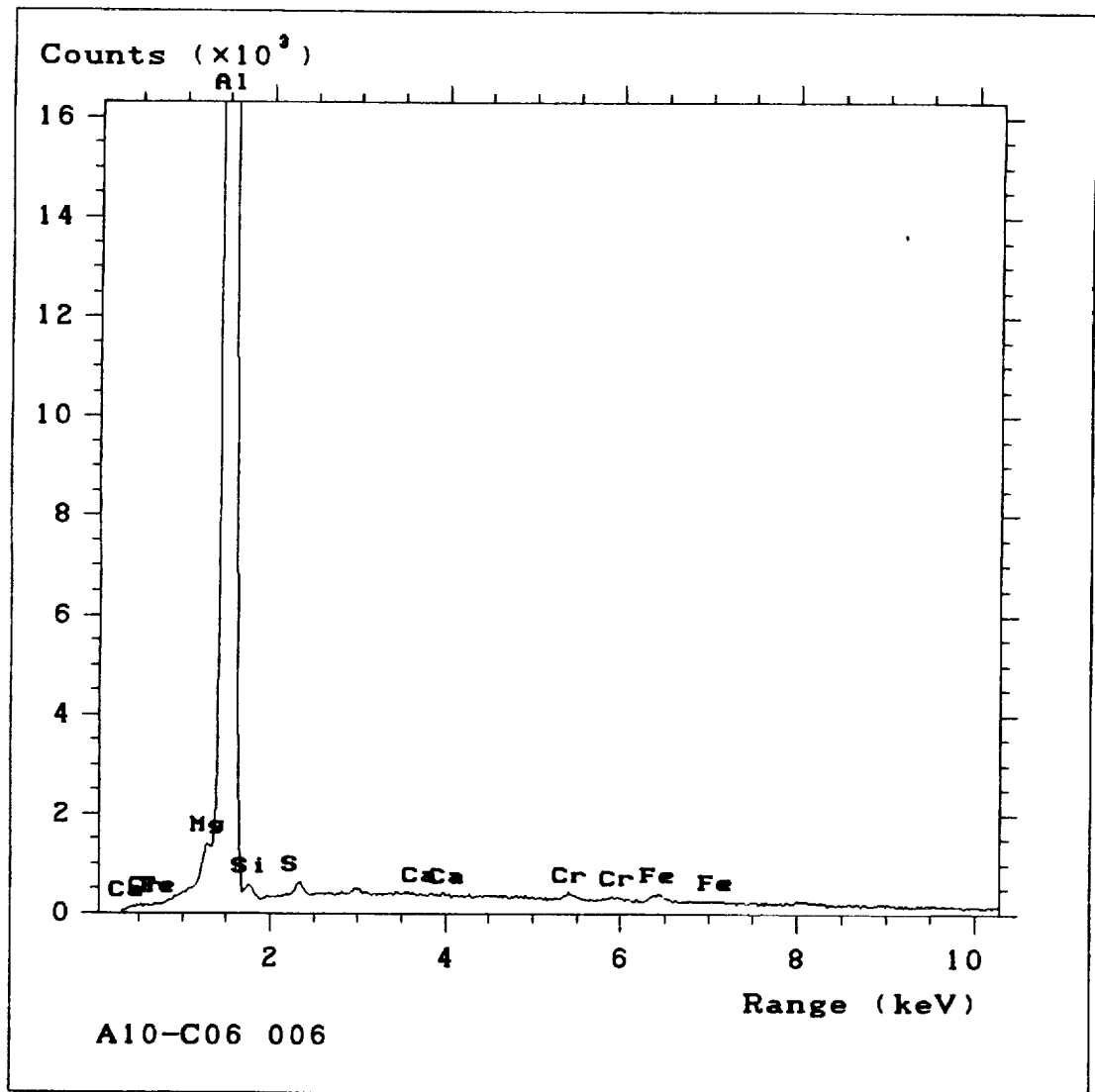


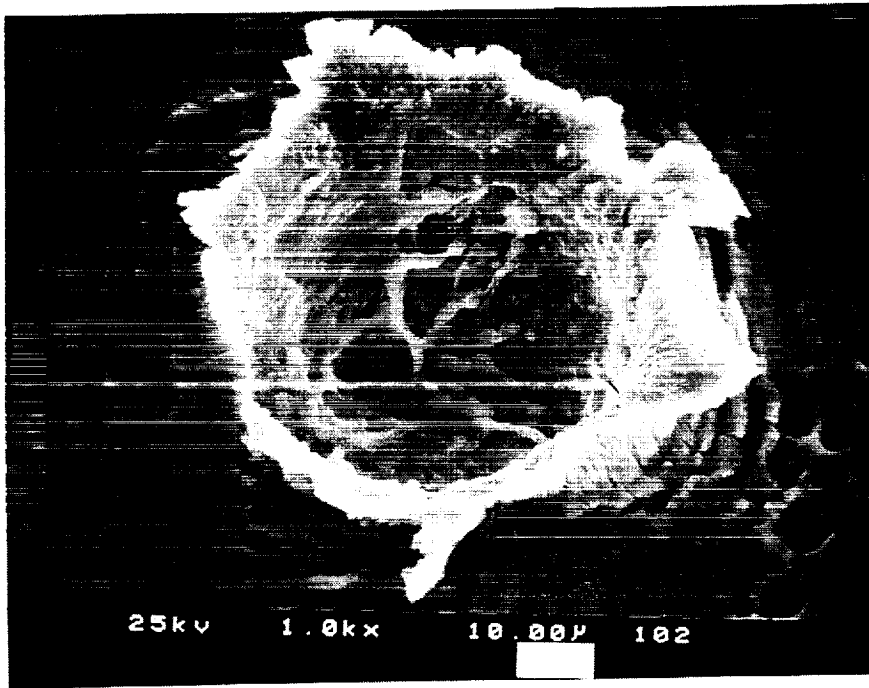
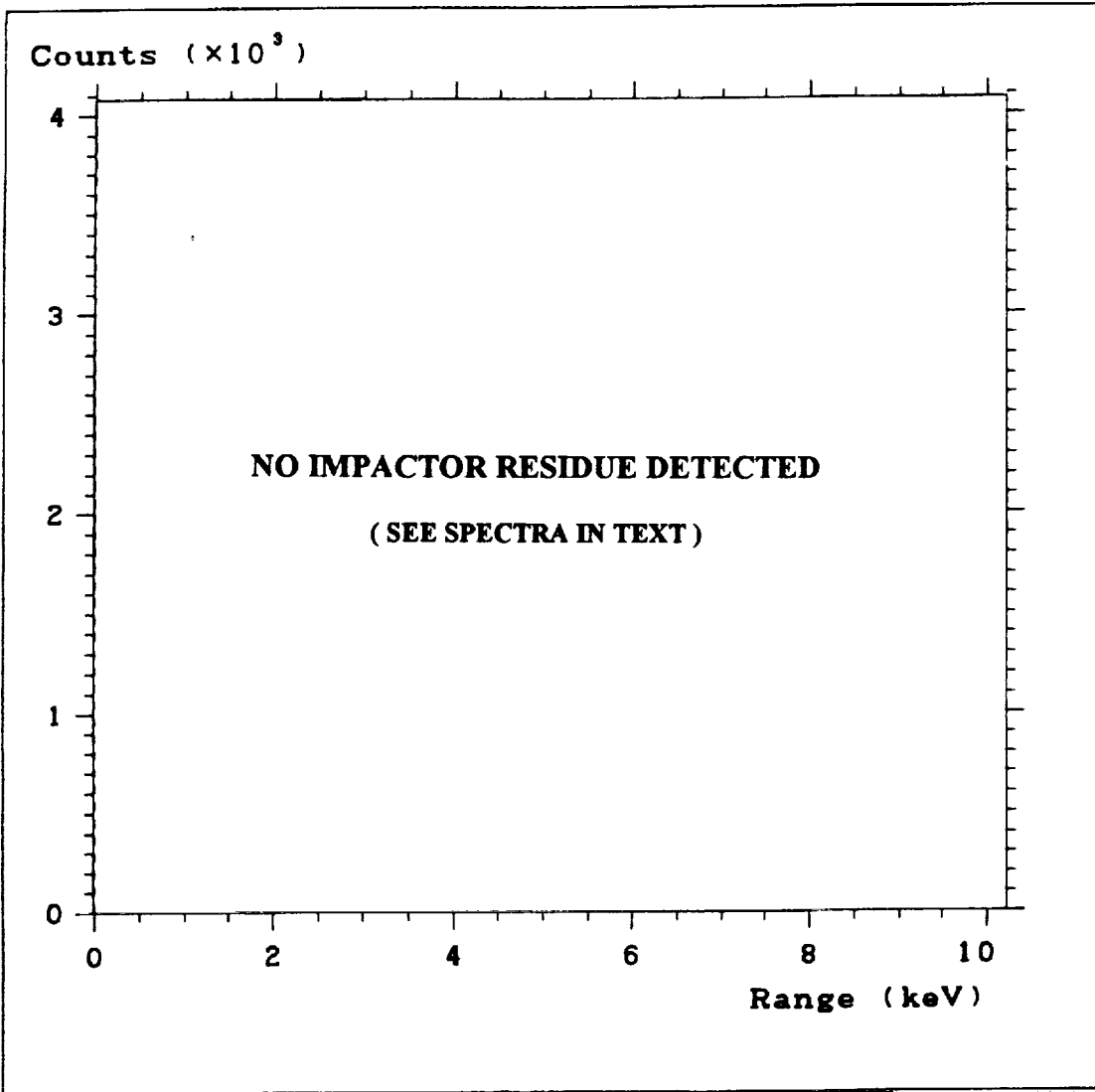


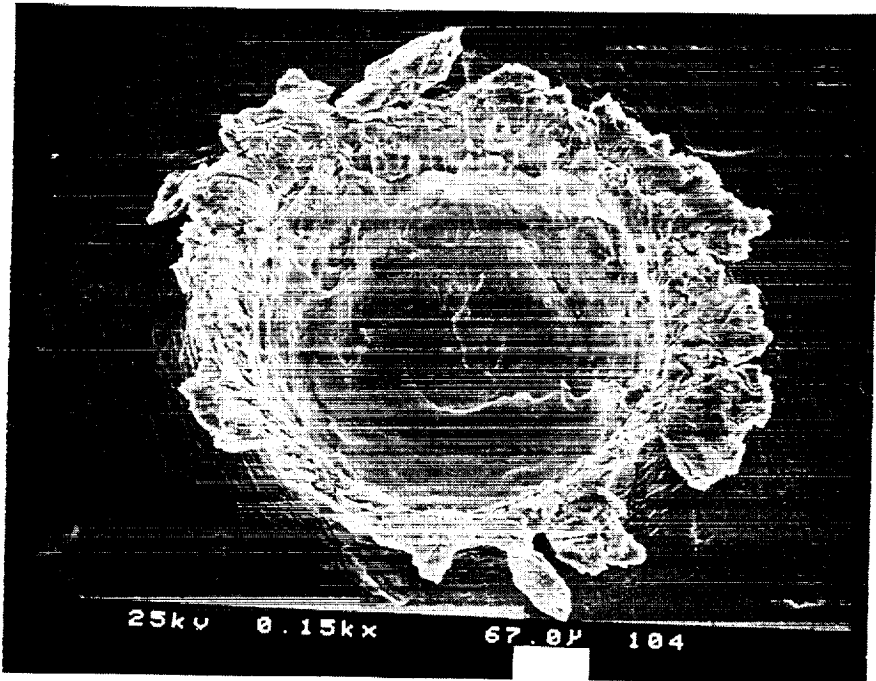
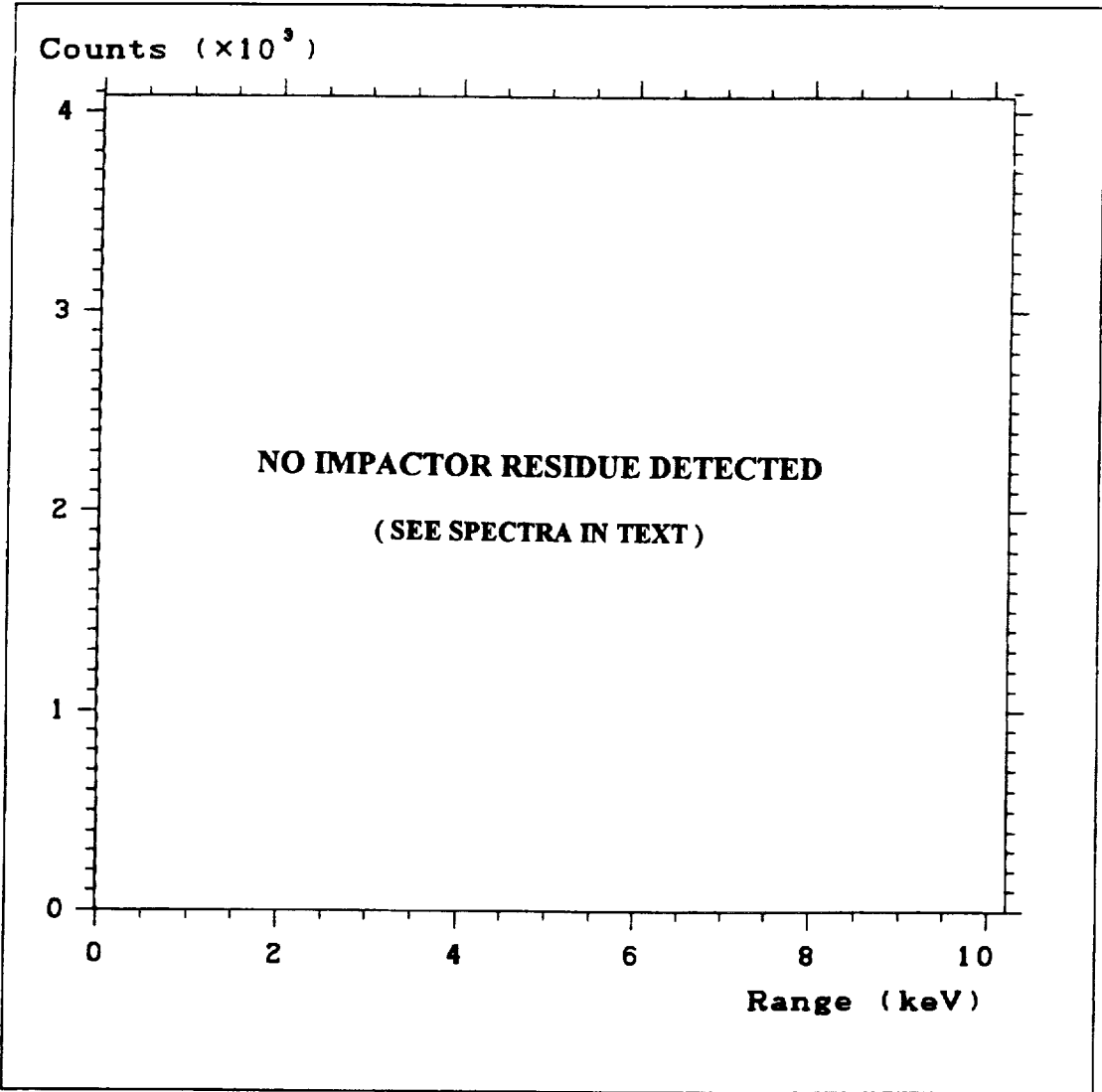


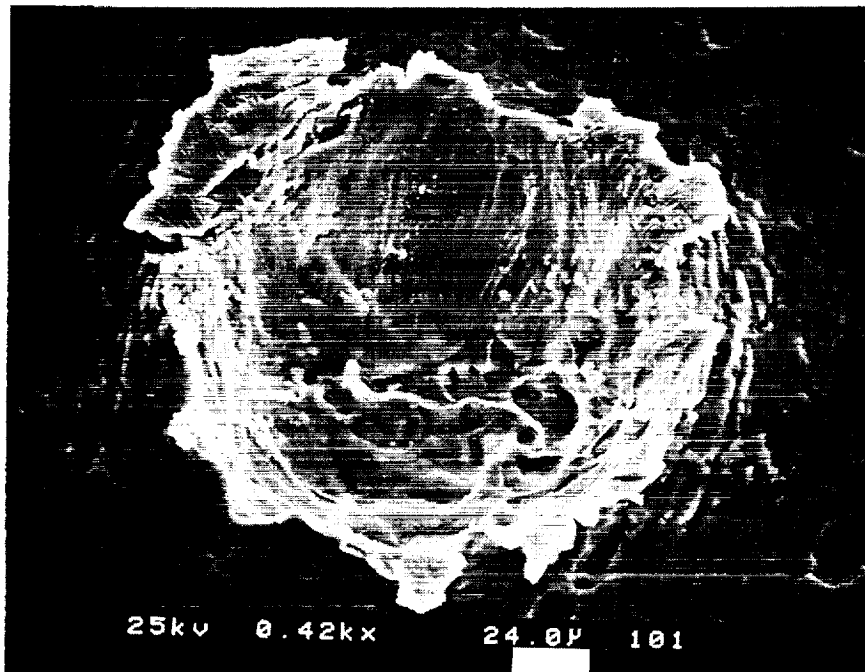
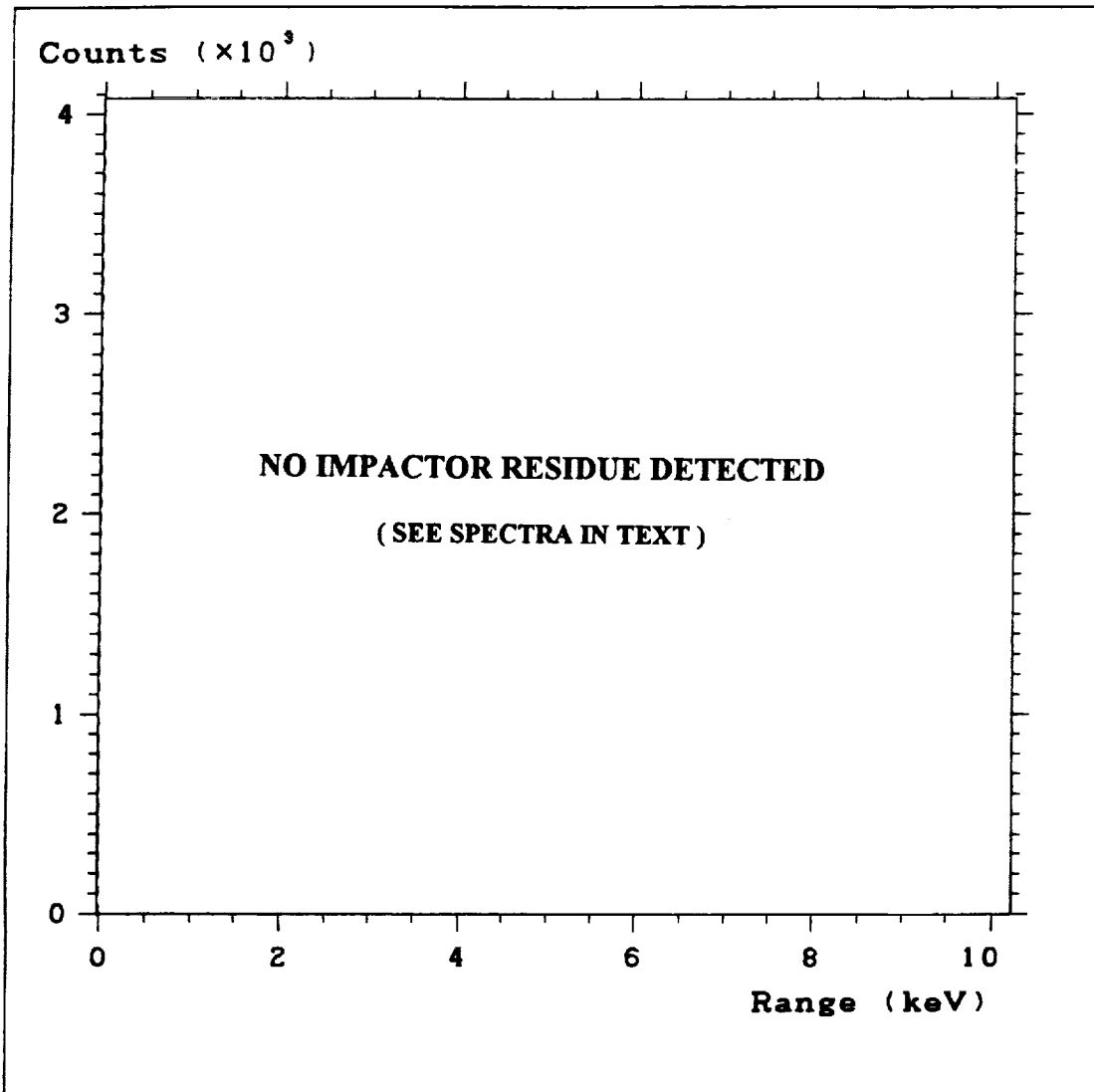






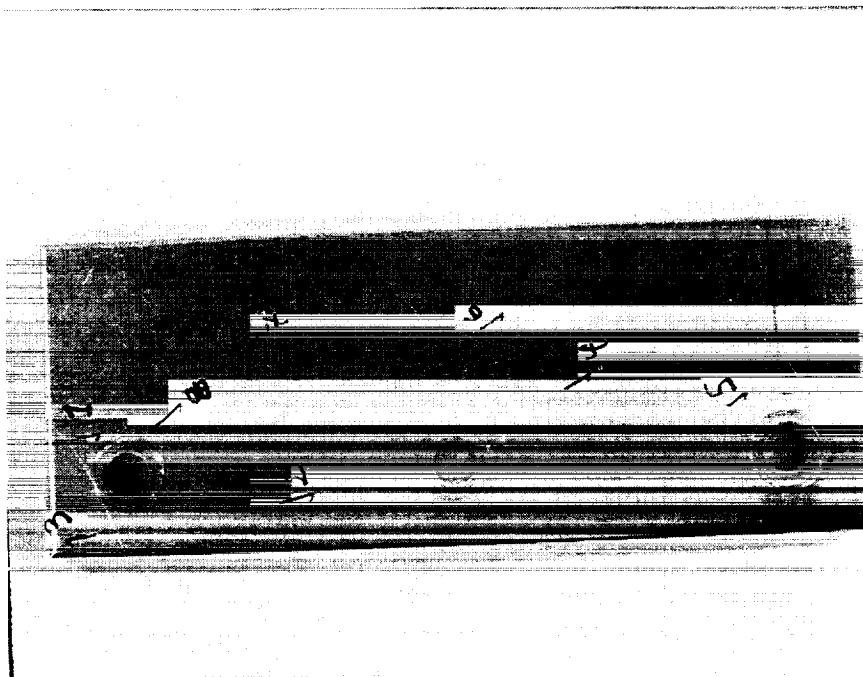


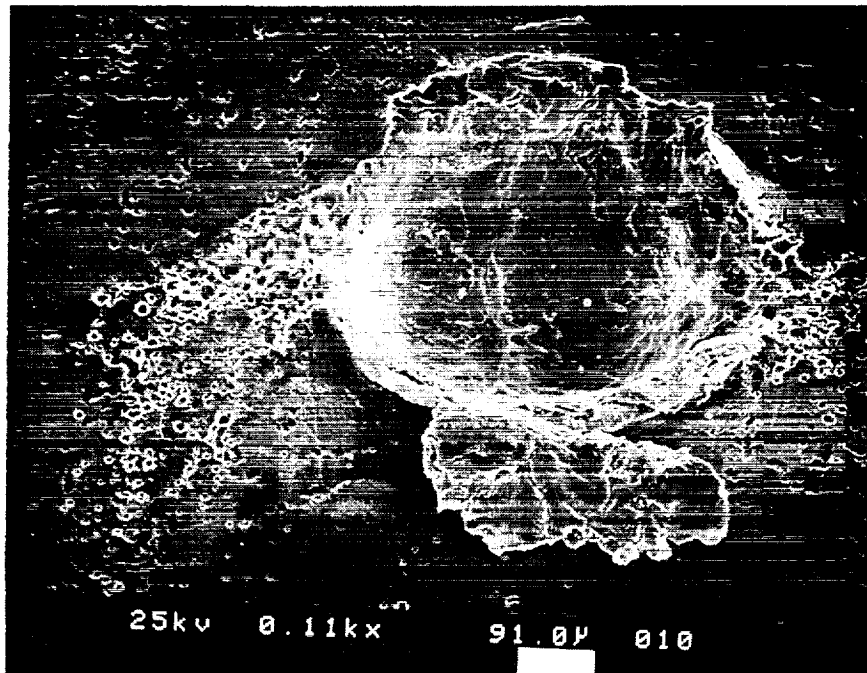
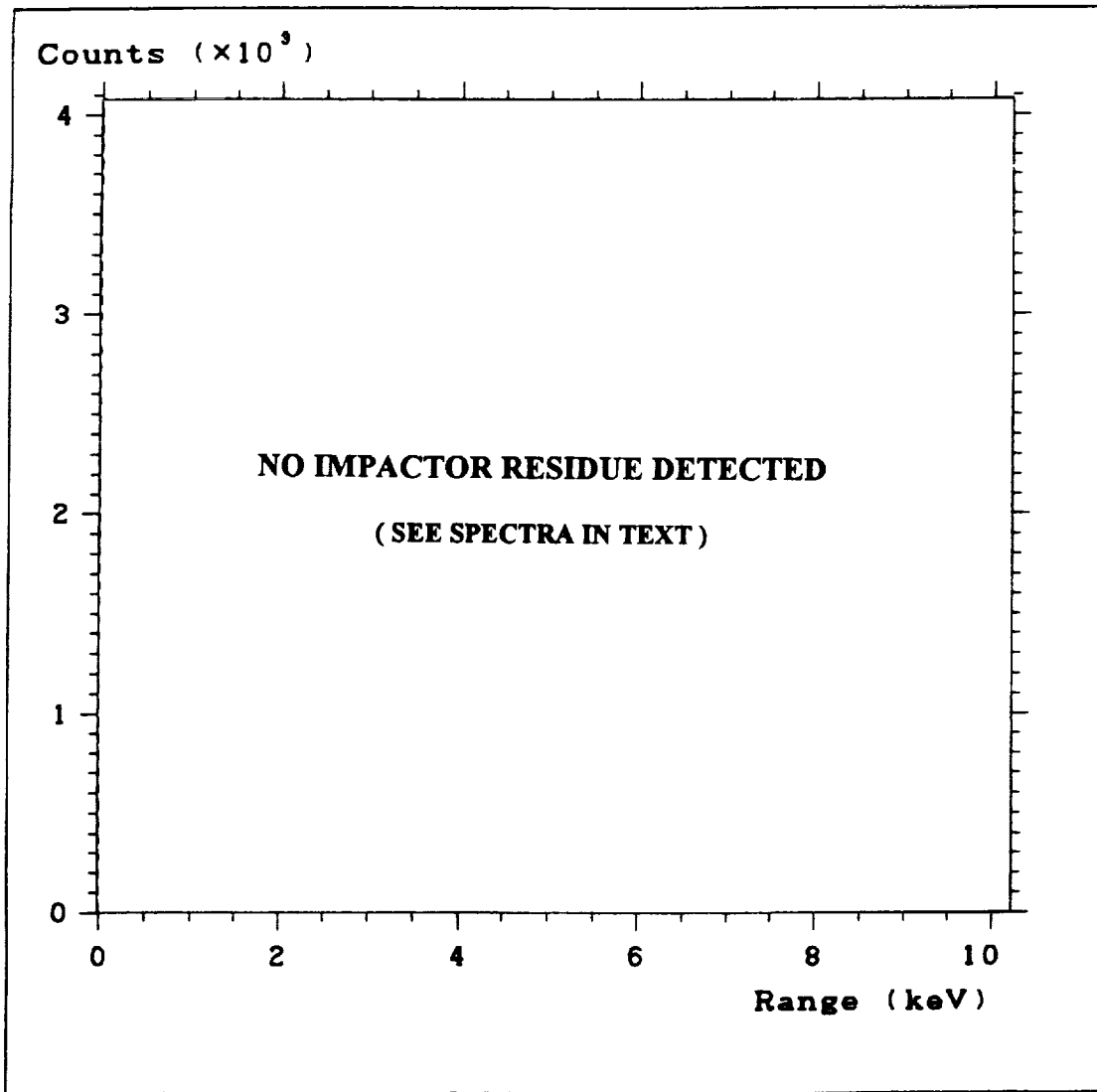


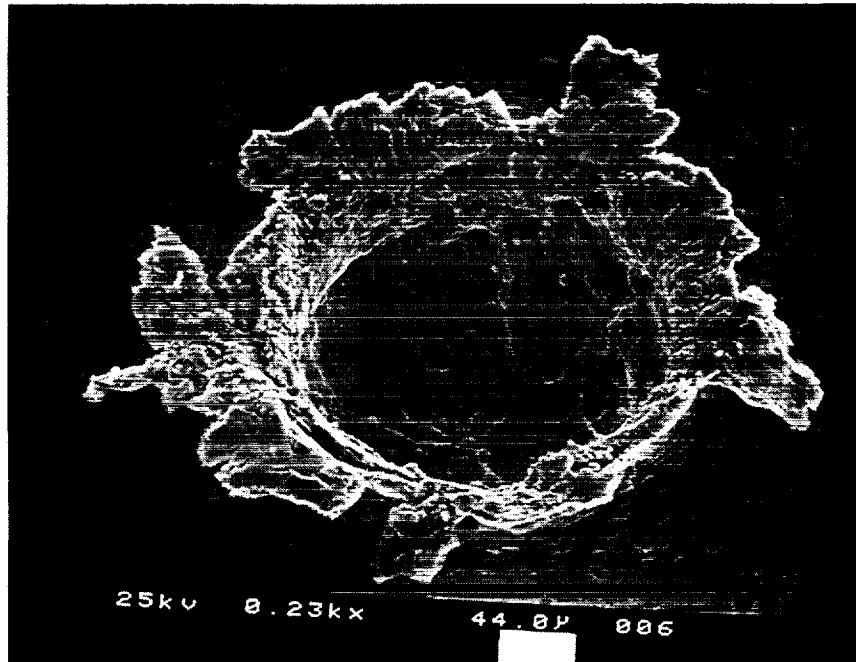
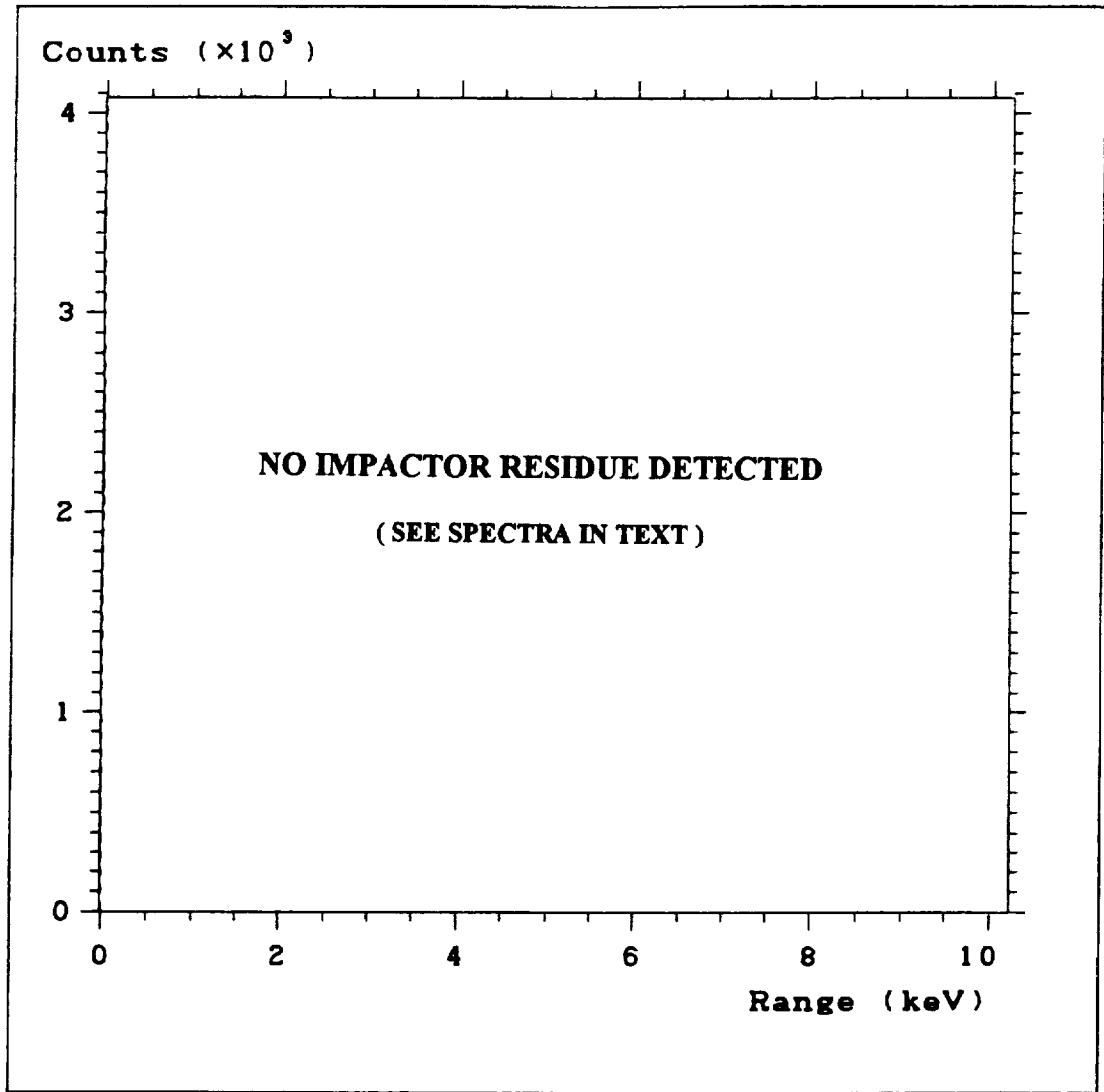


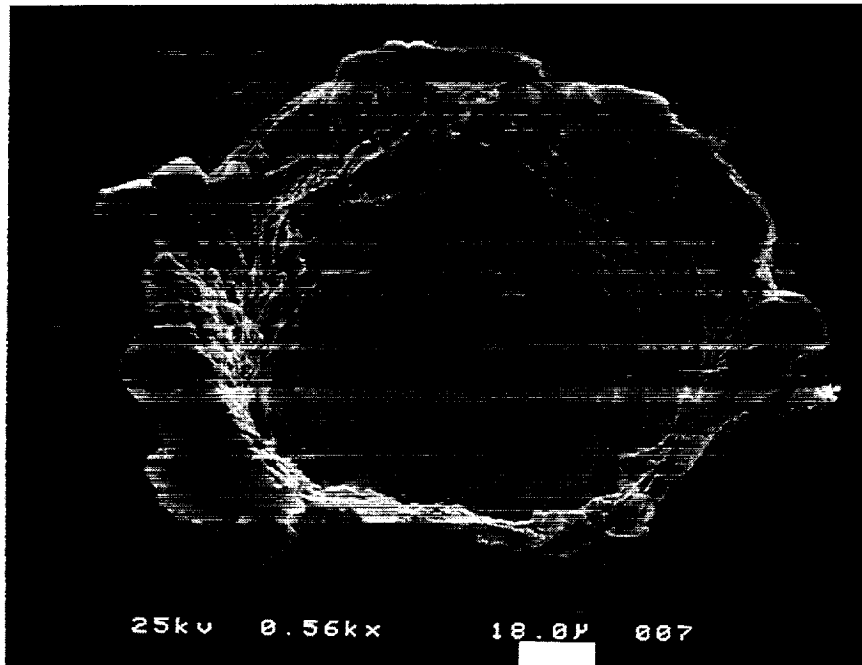
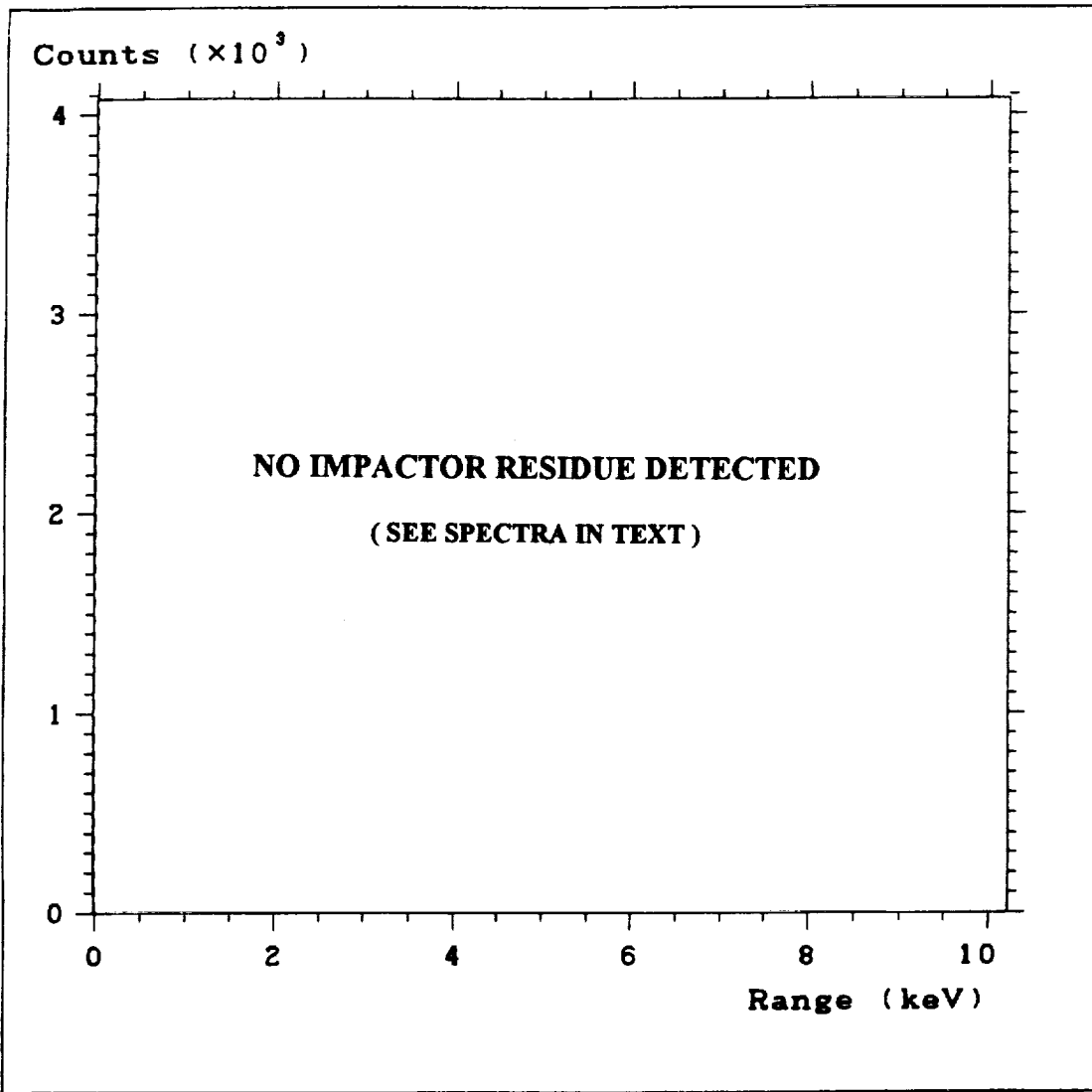
CLAMP NUMBER A10 CO8

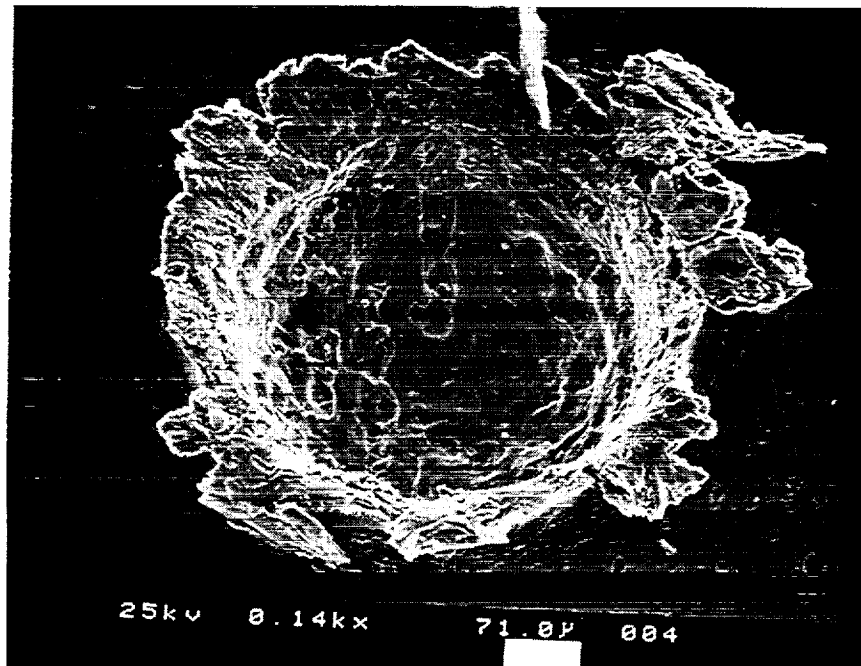
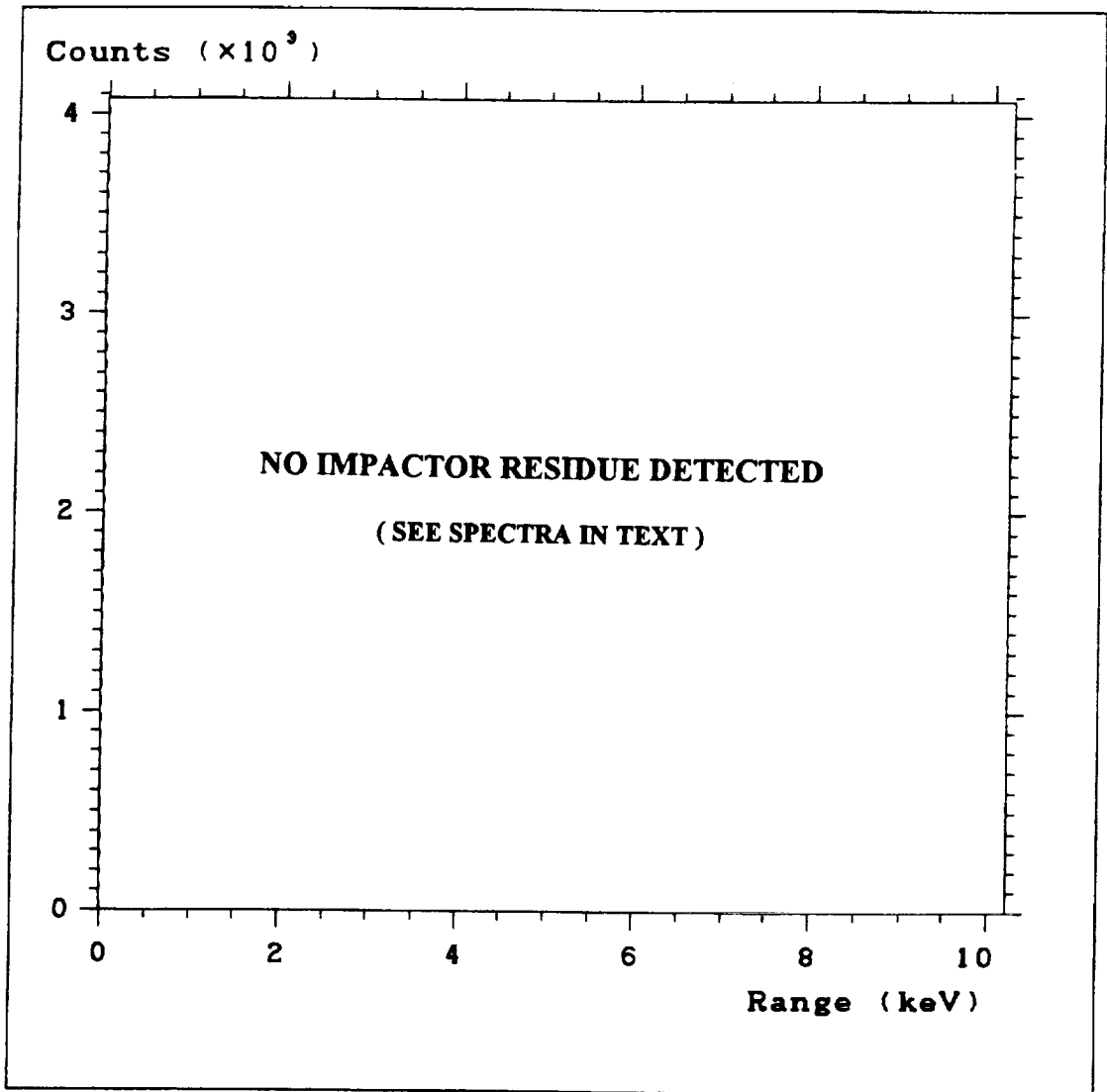
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	500	Unknown
002	260	Unknown
003	140	Unknown
004	500	Unknown
005	100	Unknown
006	120	Unknown
007	140	Unknown
008	70	Unknown

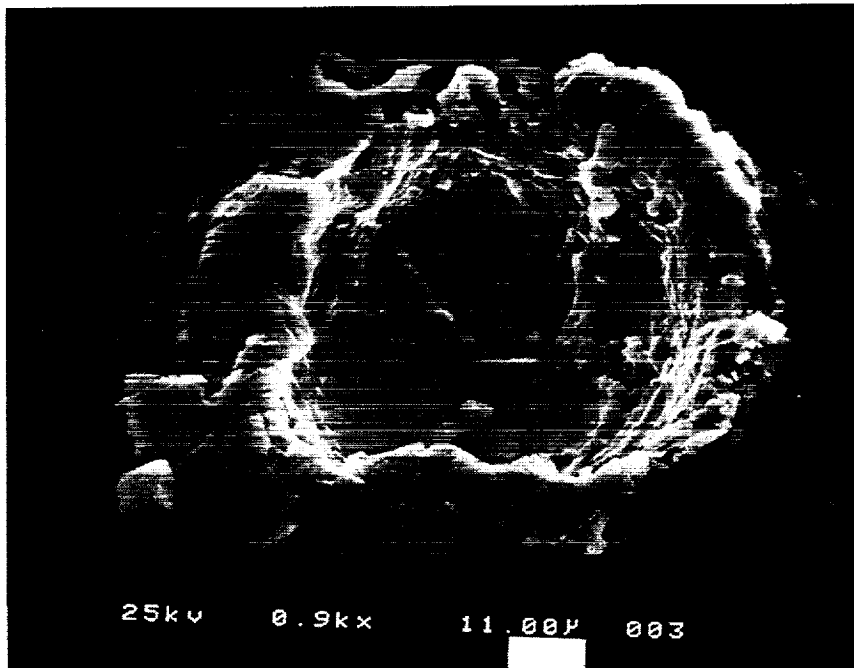
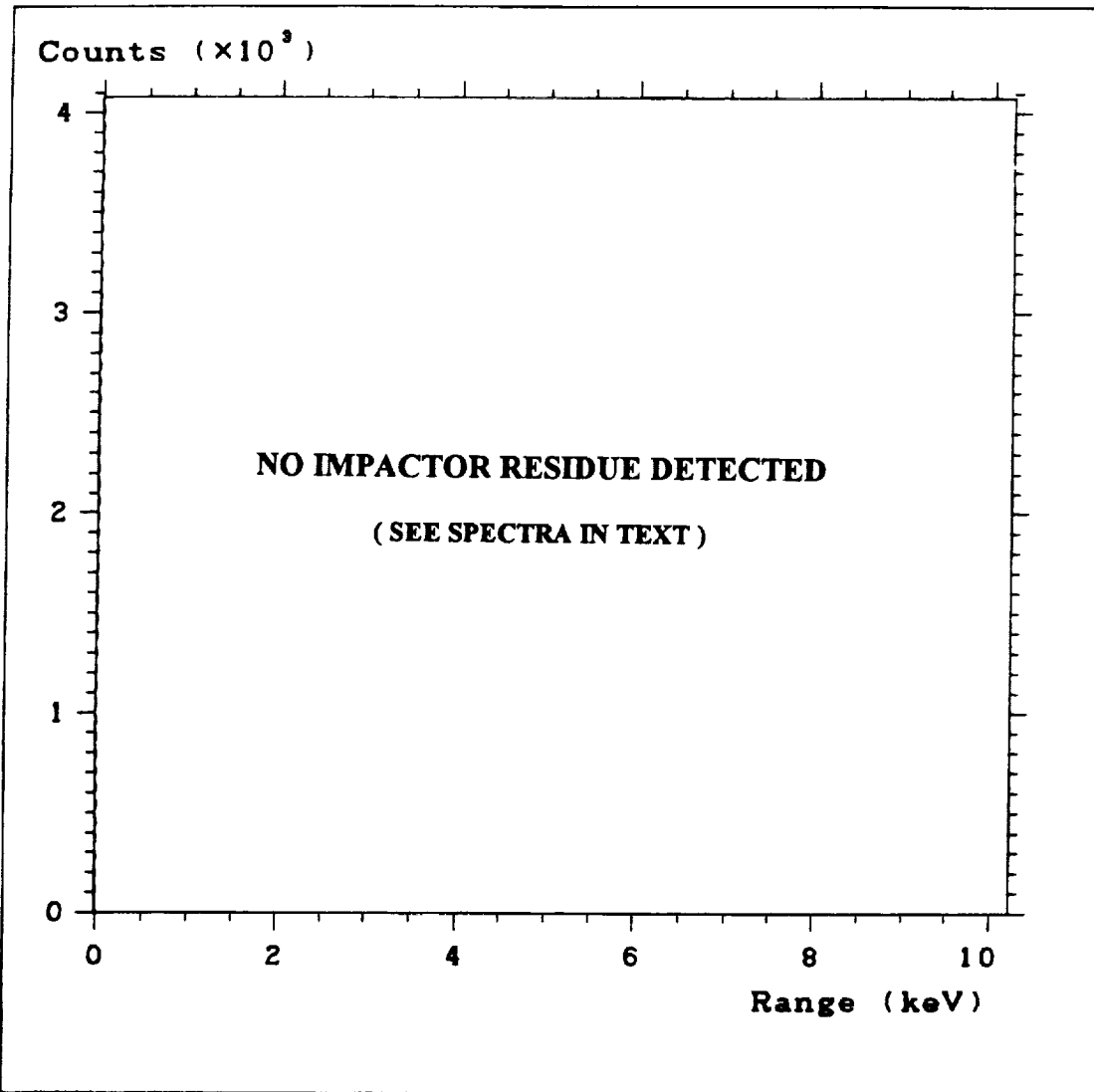


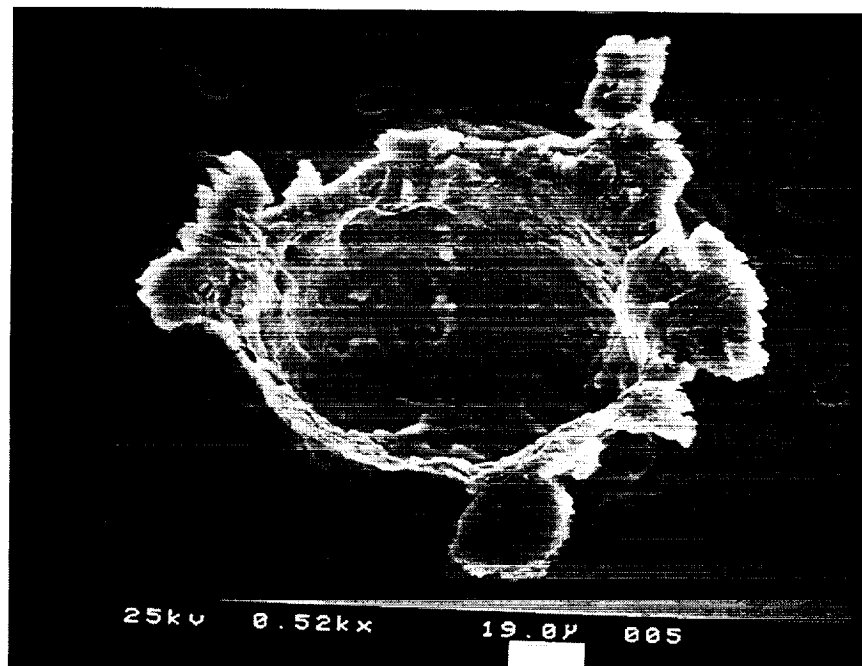
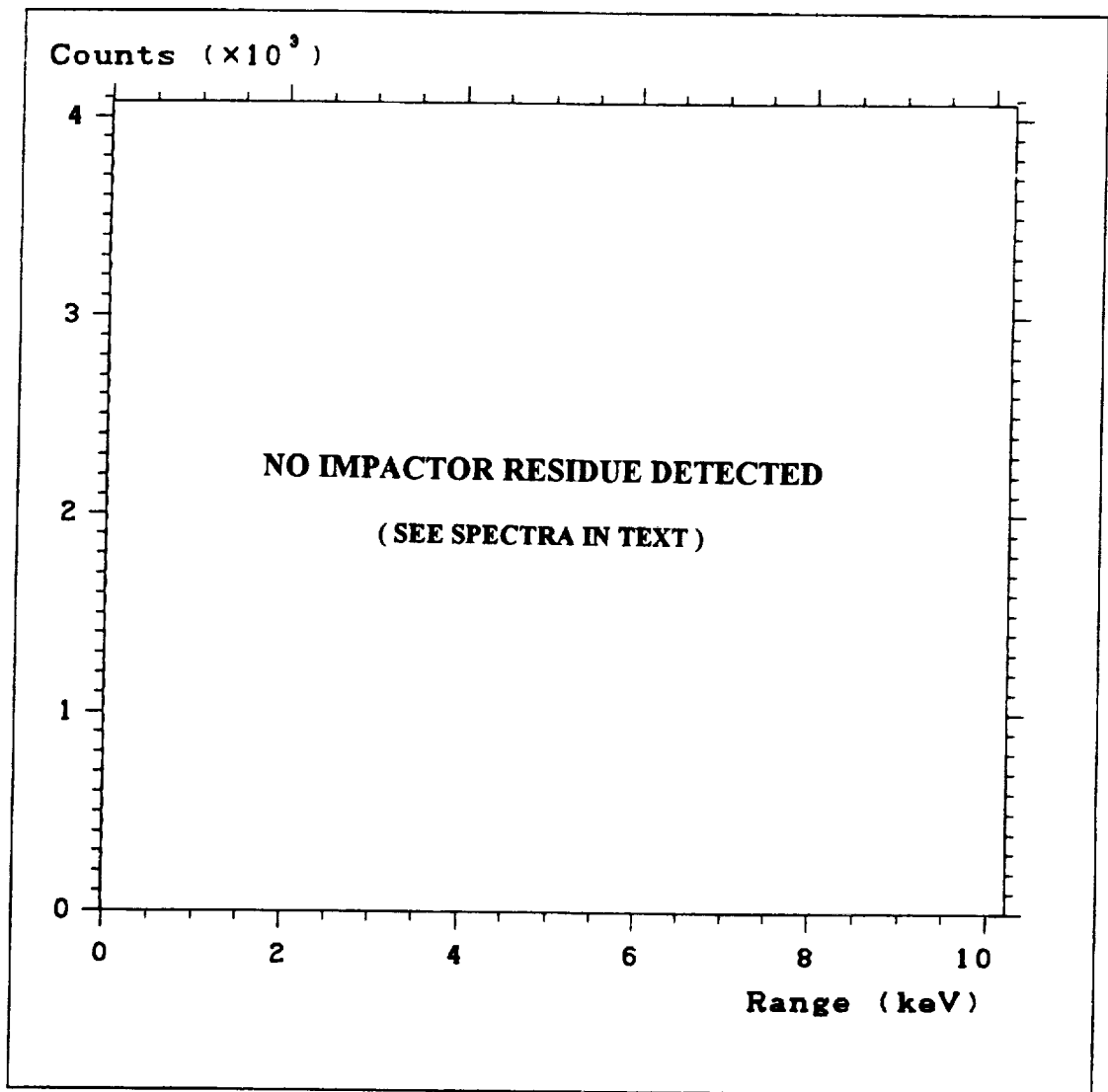


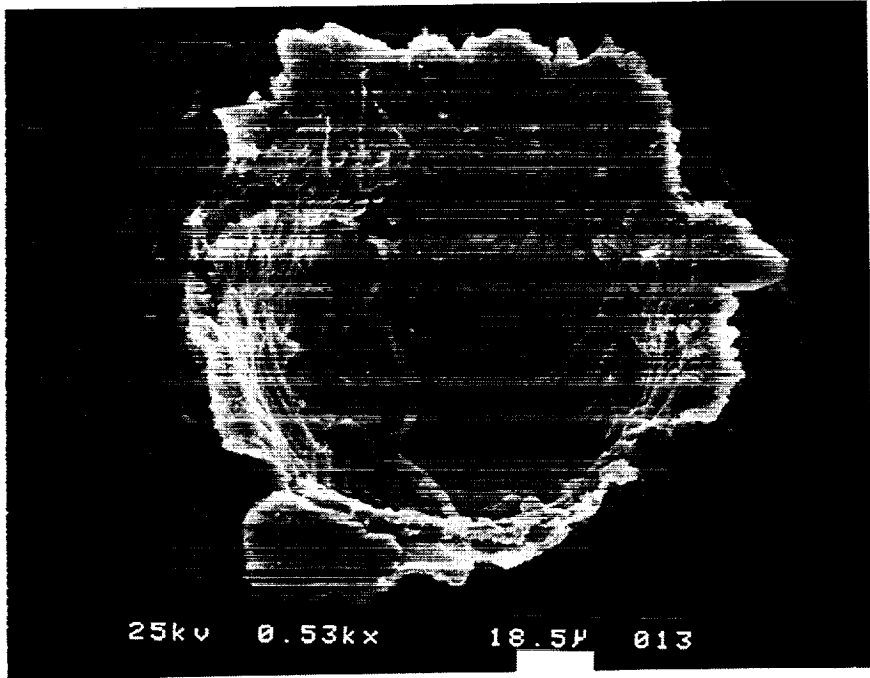
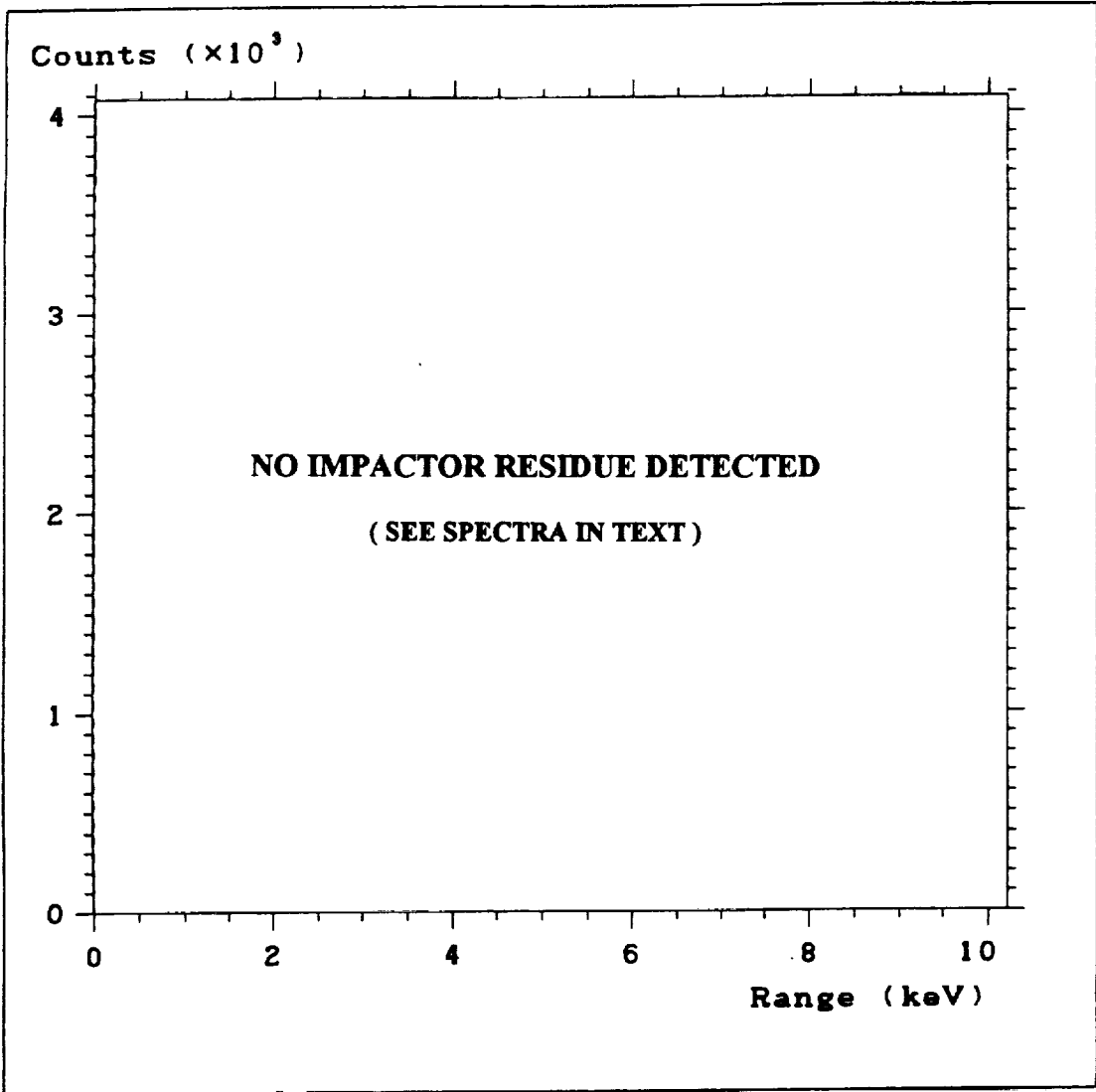


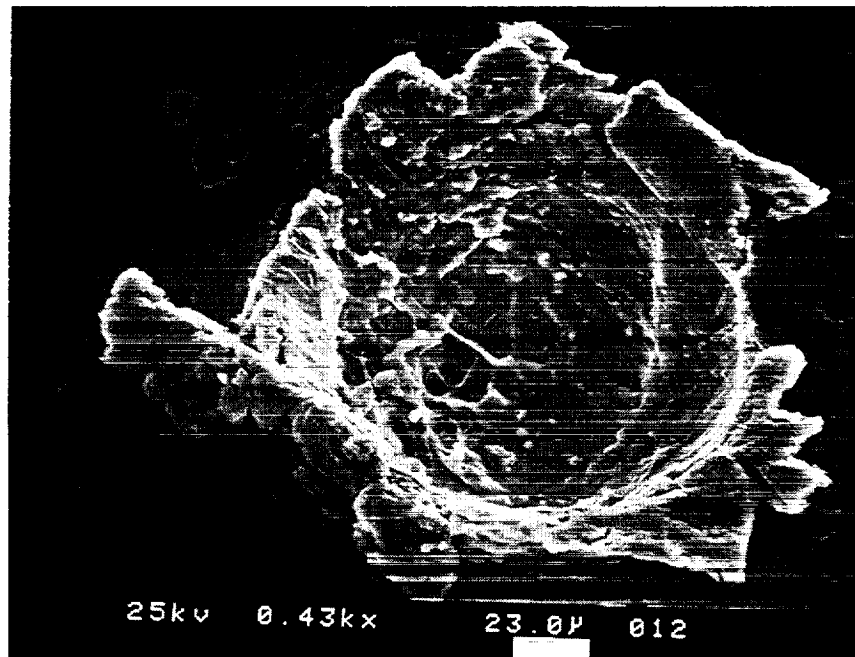
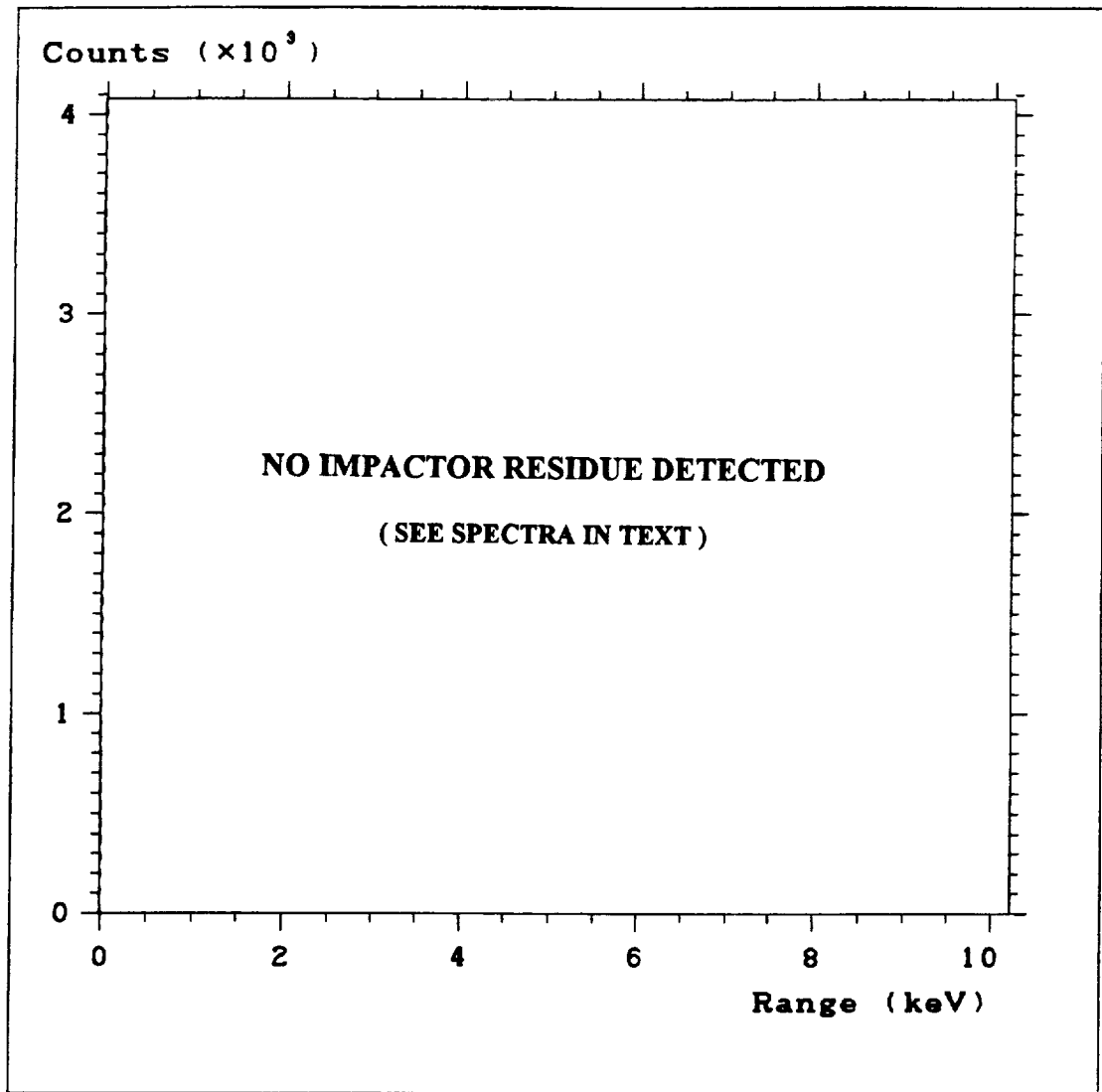






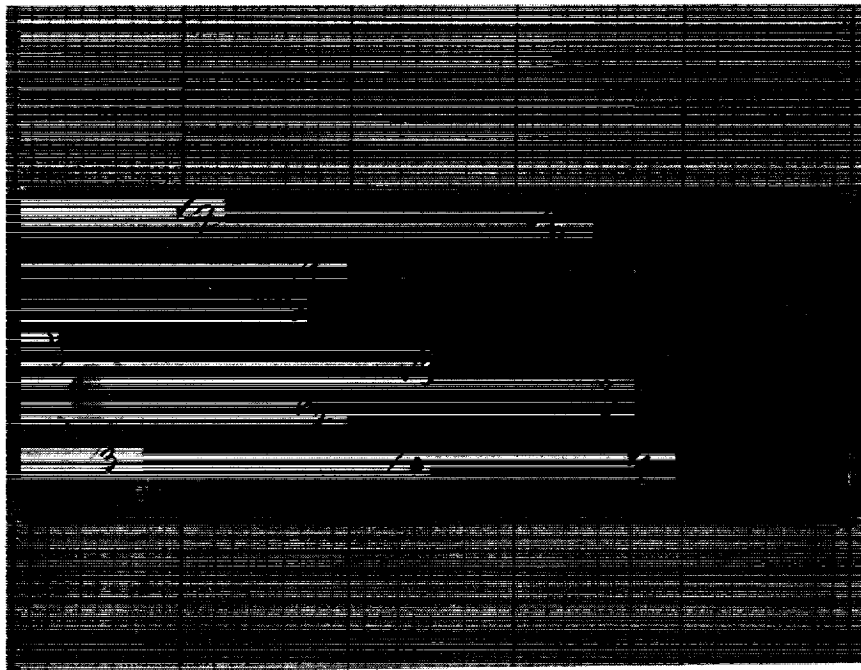


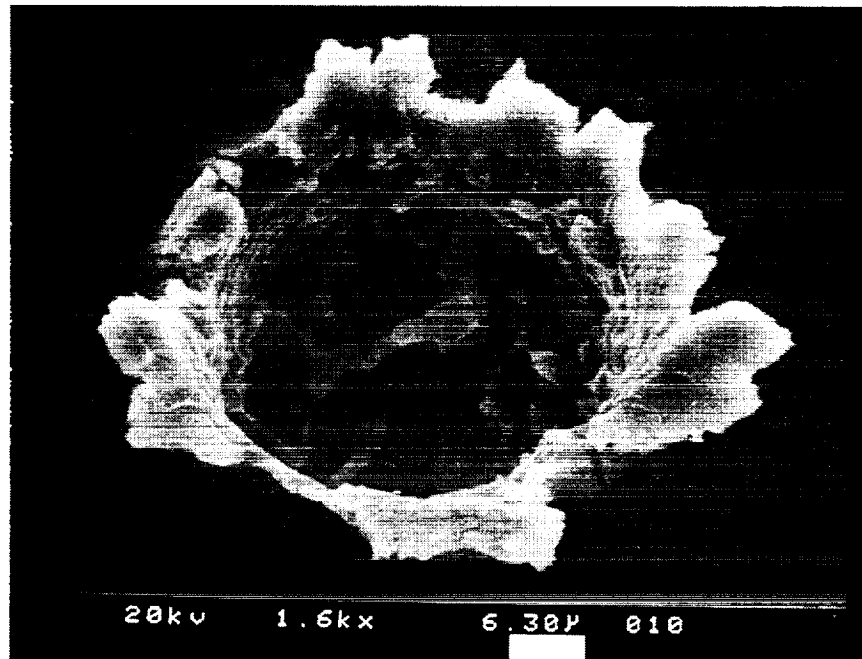
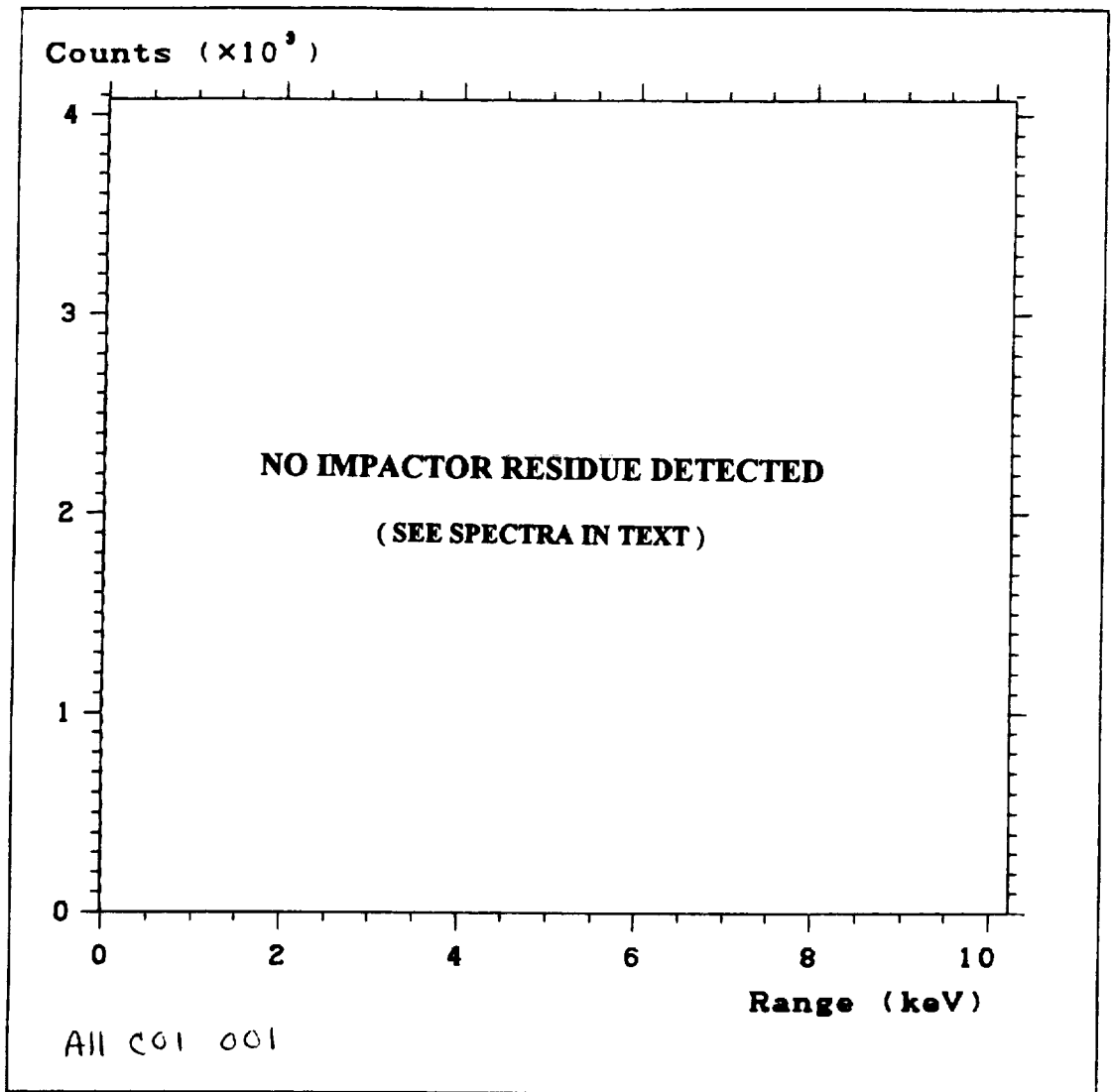


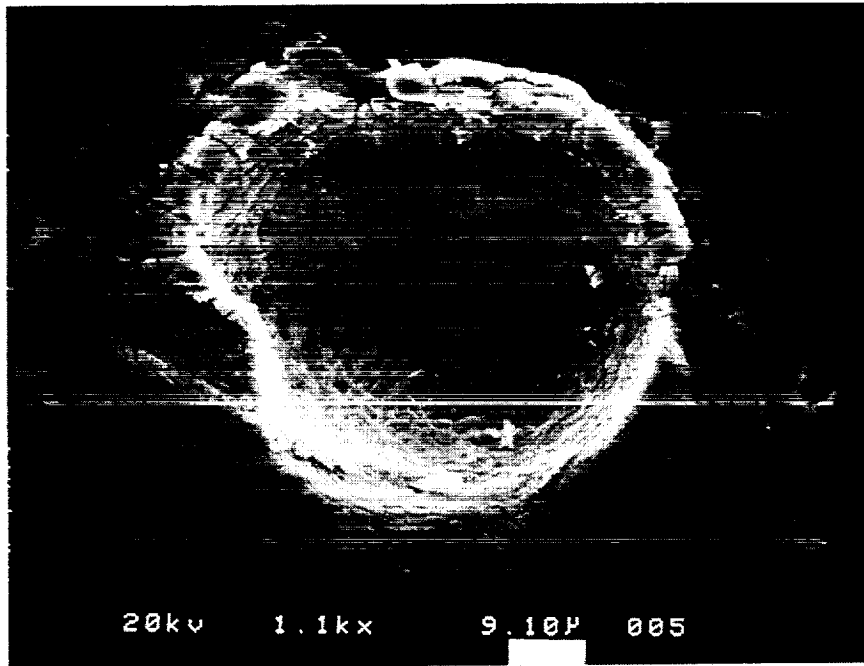
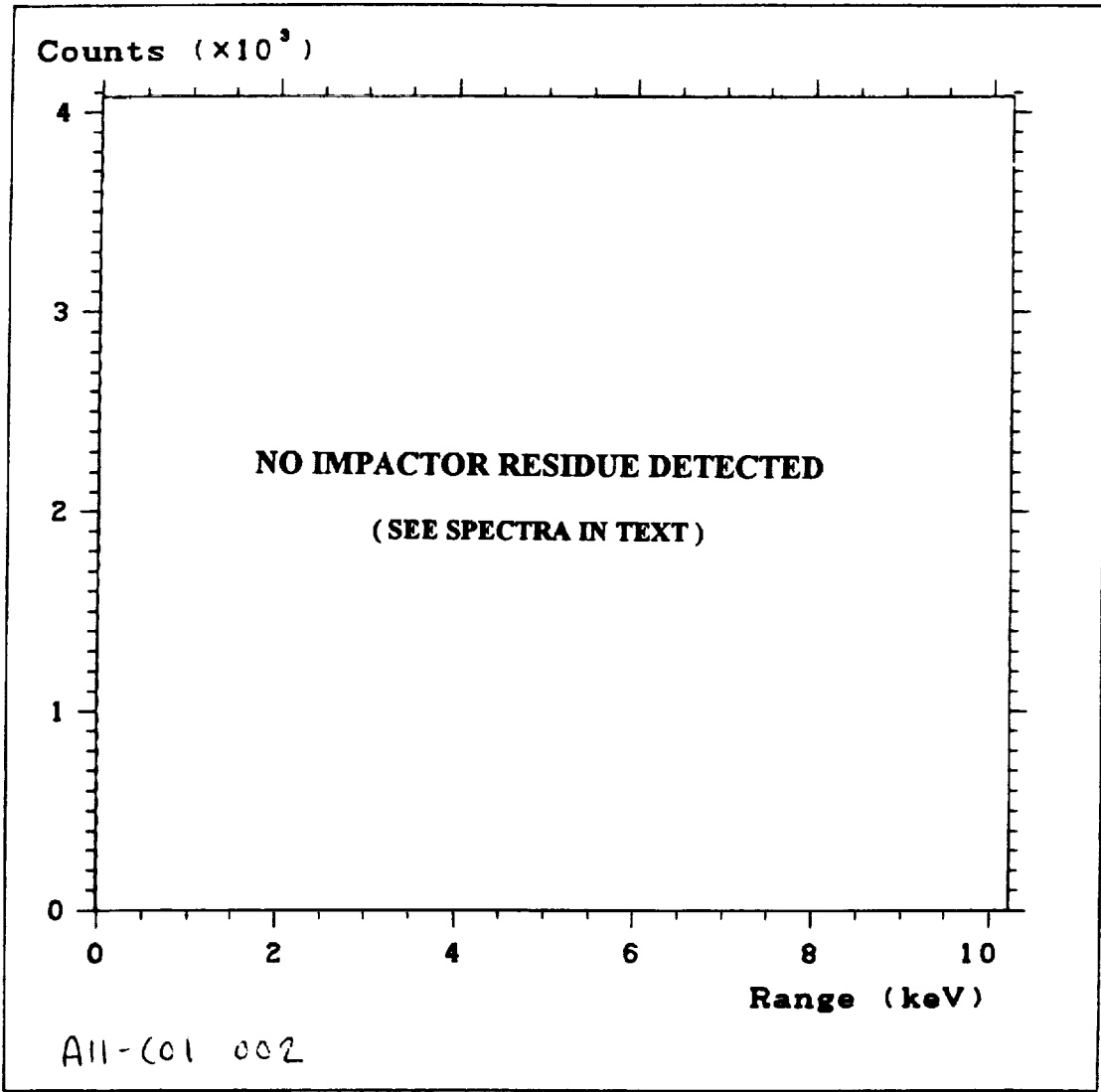


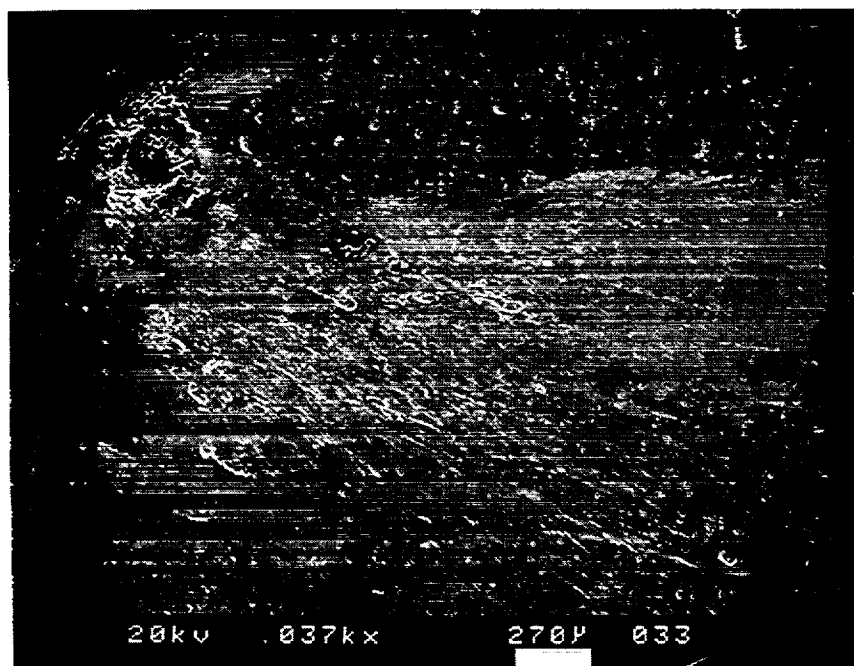
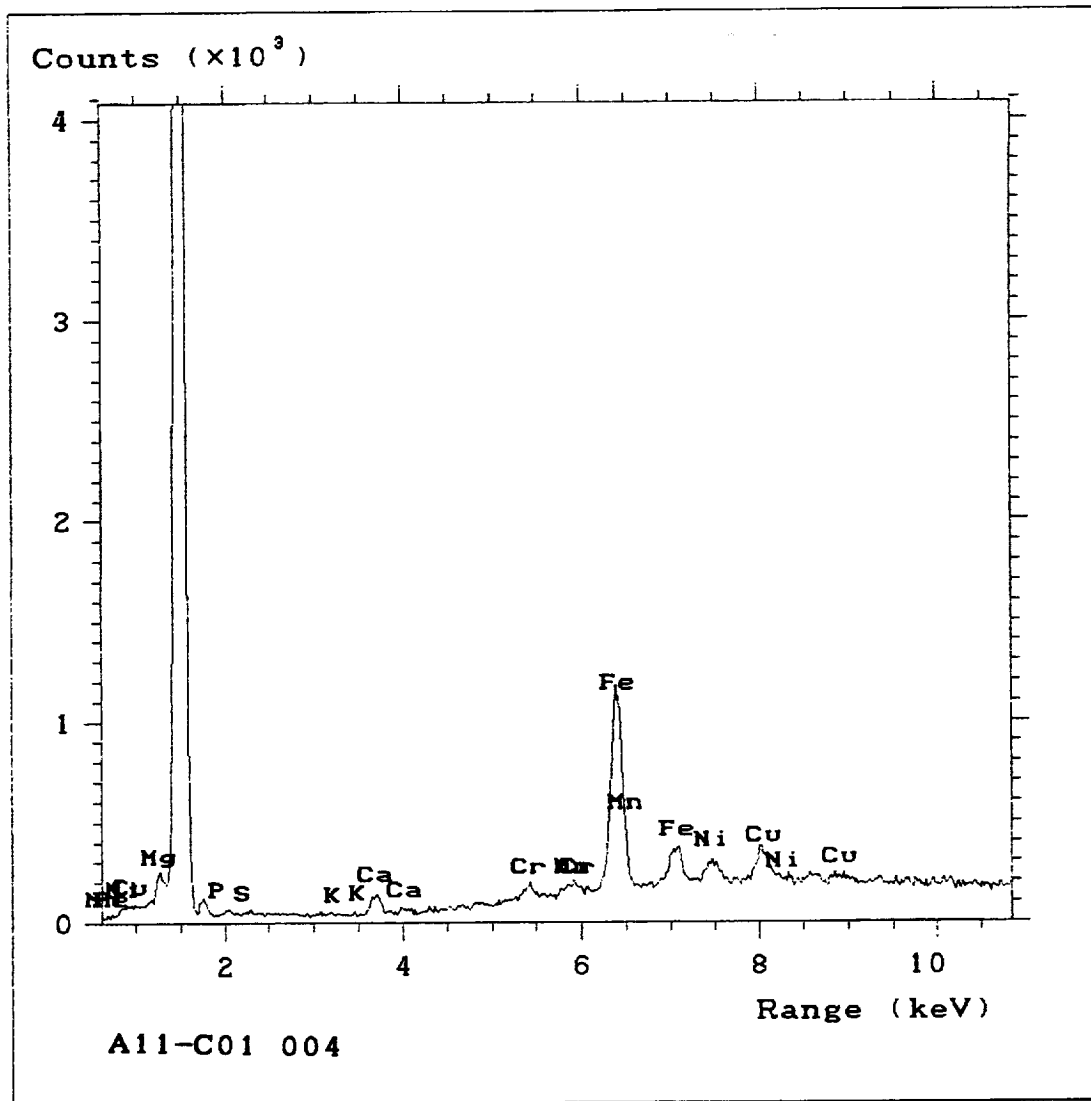
CLAMP NUMBER A11 C01

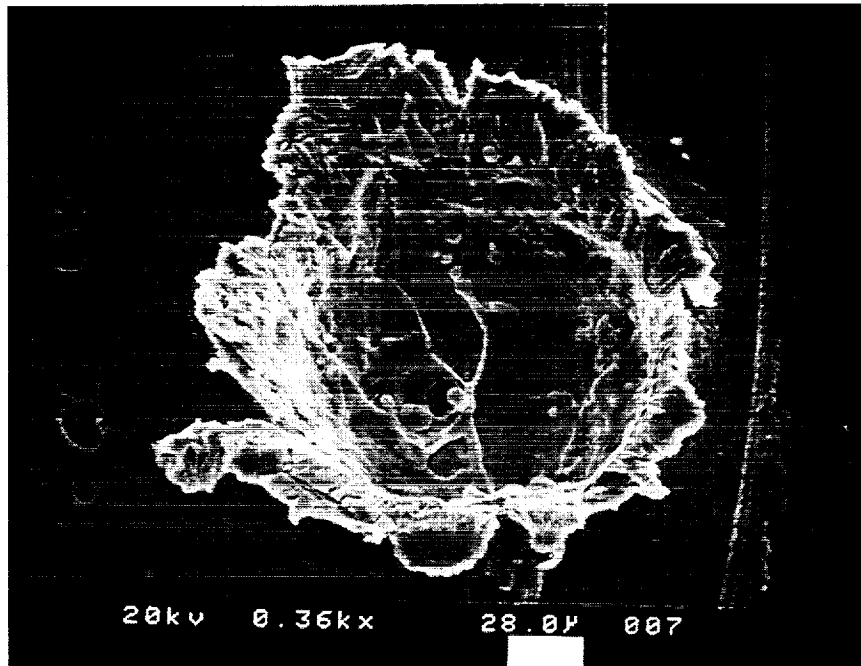
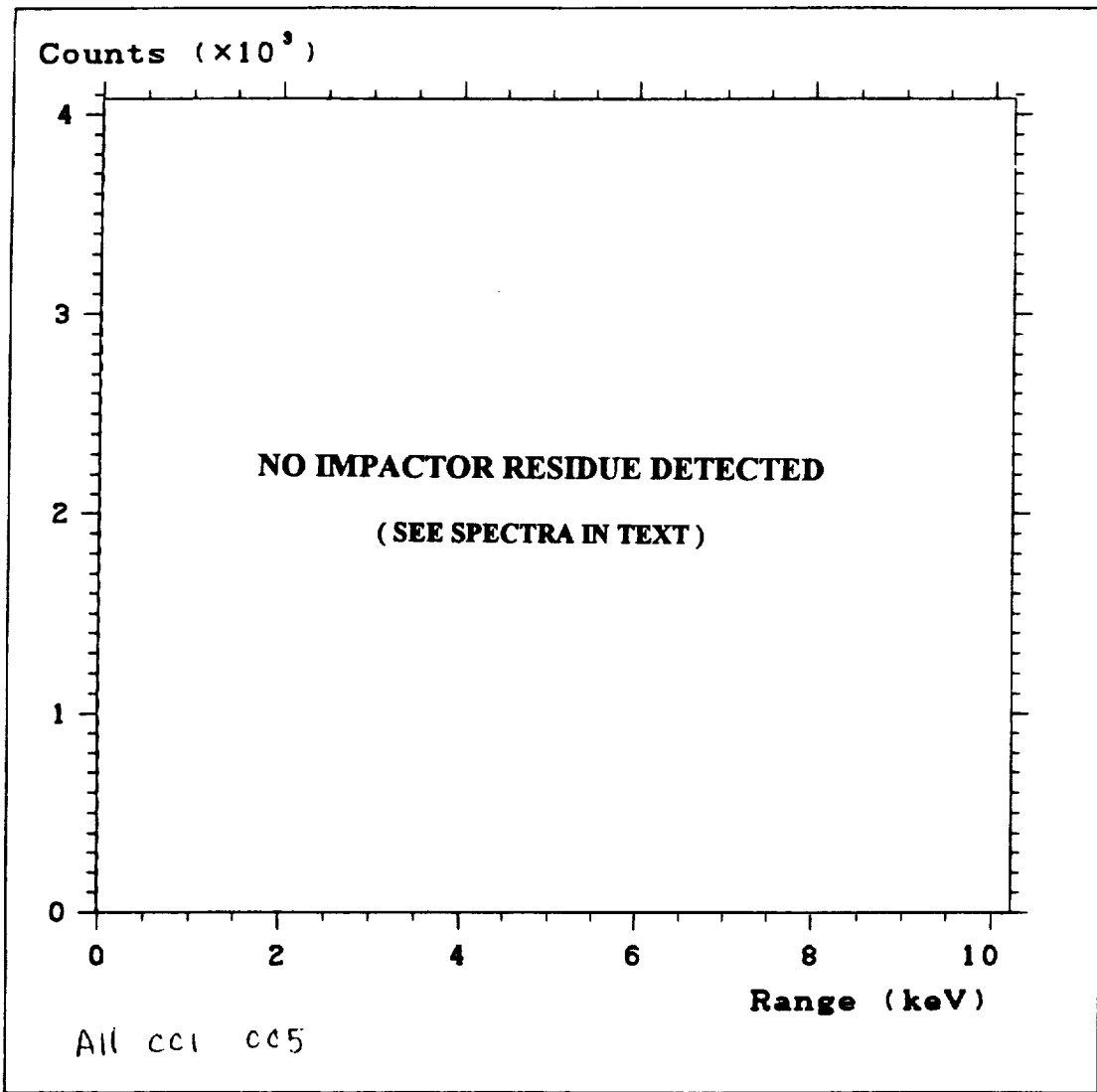
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	60	Unknown
002	50	Flaw
003	60	Unknown
004	130	Bolt Spray
005	180	Unknown
006	140	Unknown
007	60	Unknown
008	90	Unknown

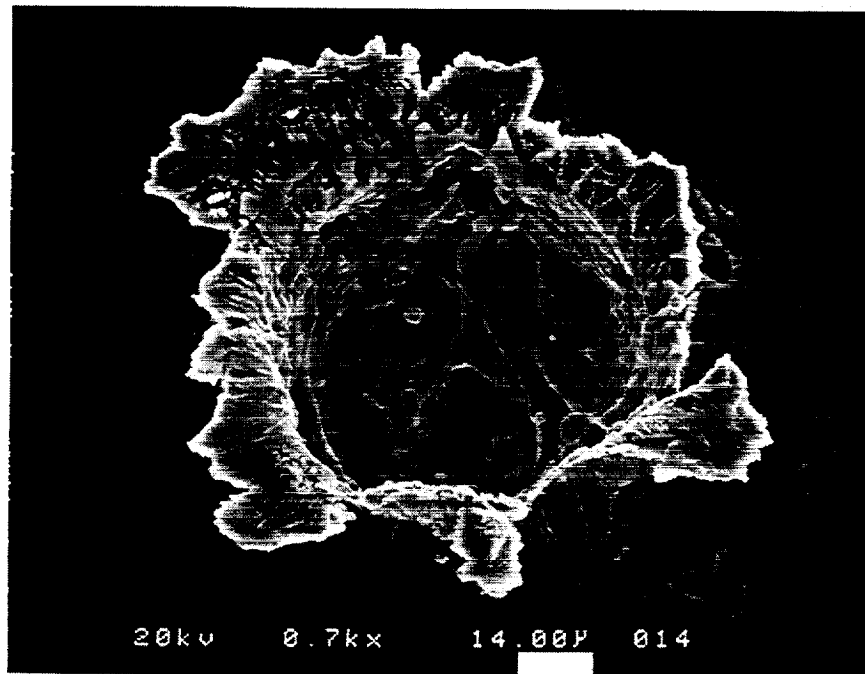
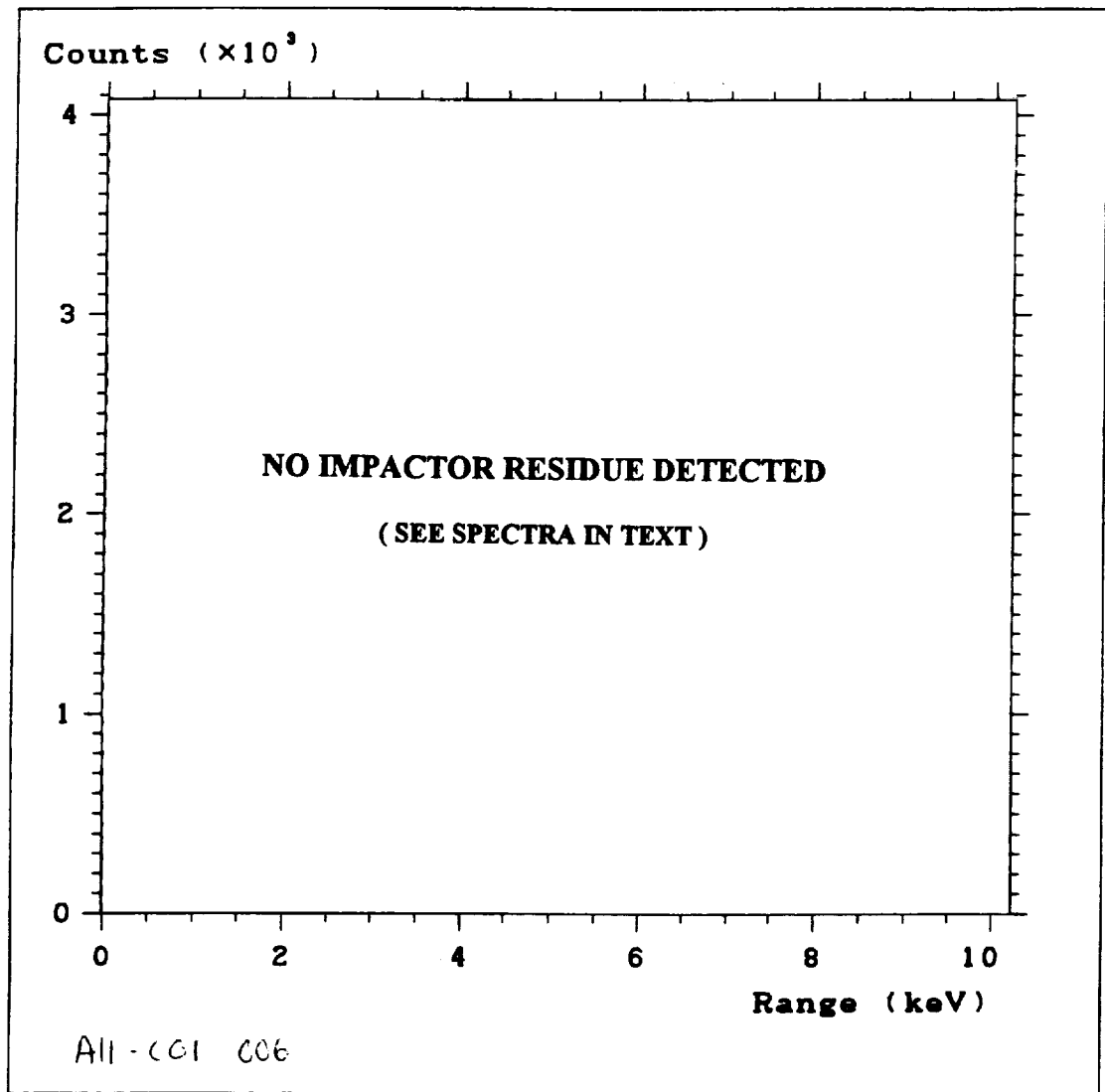


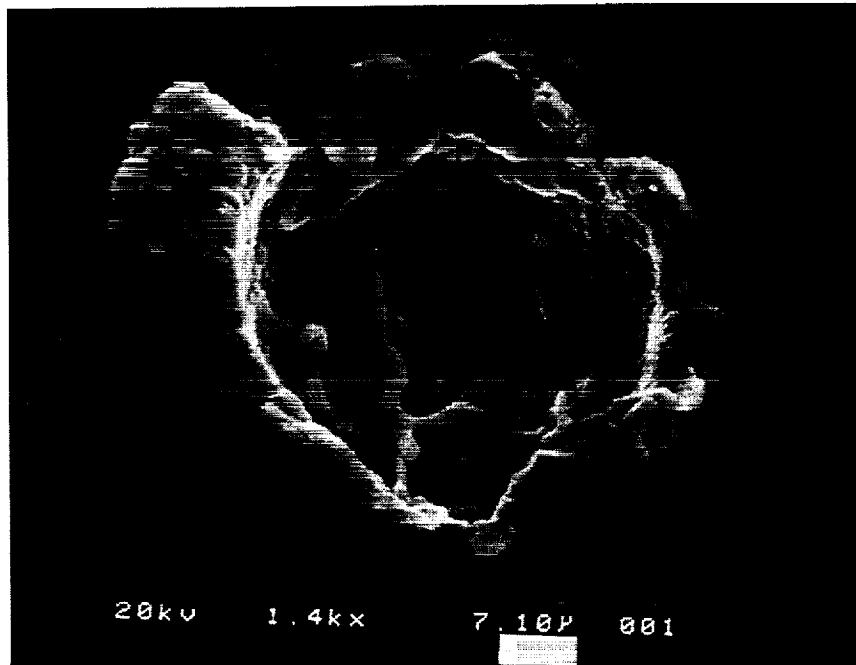
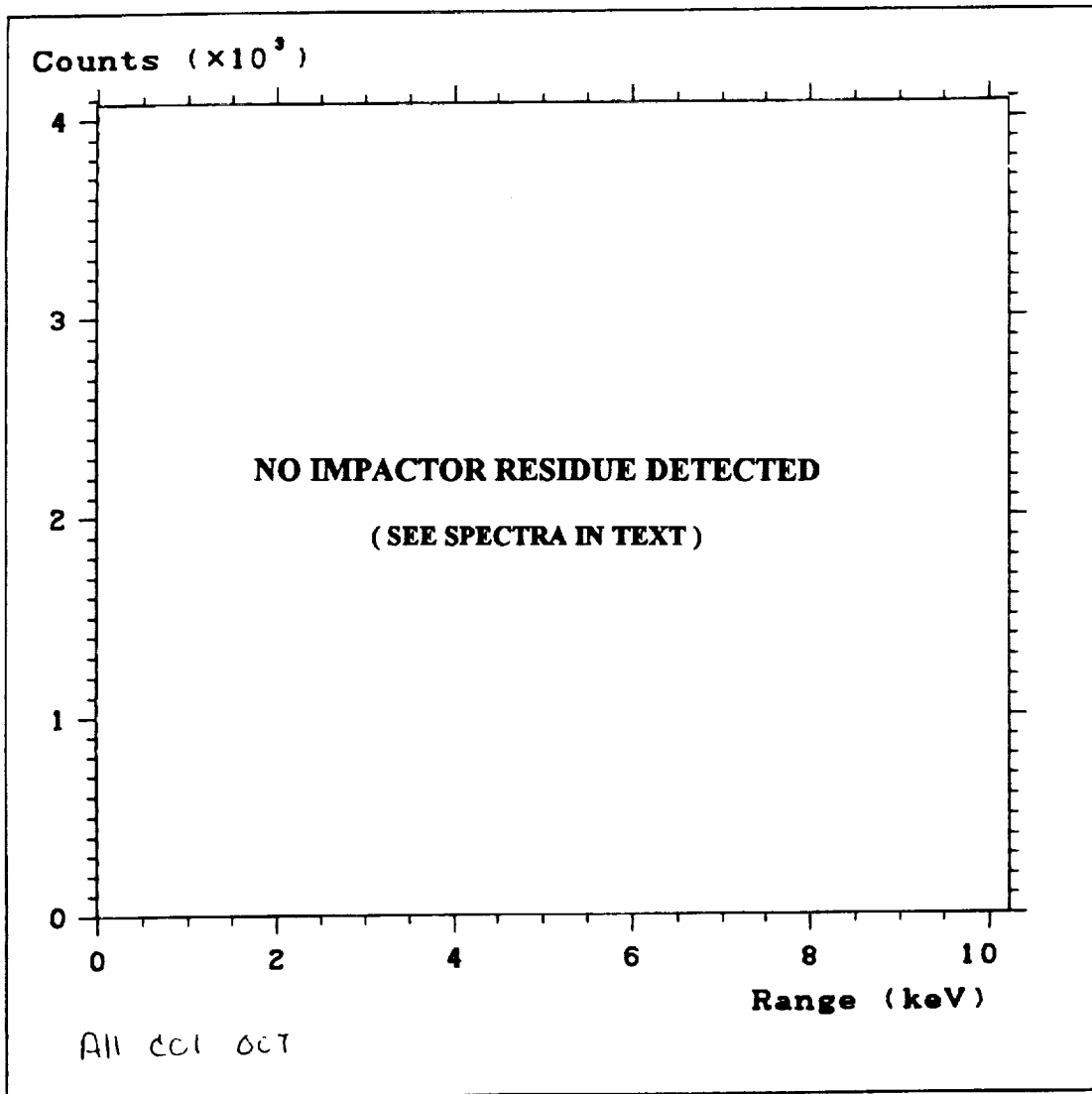


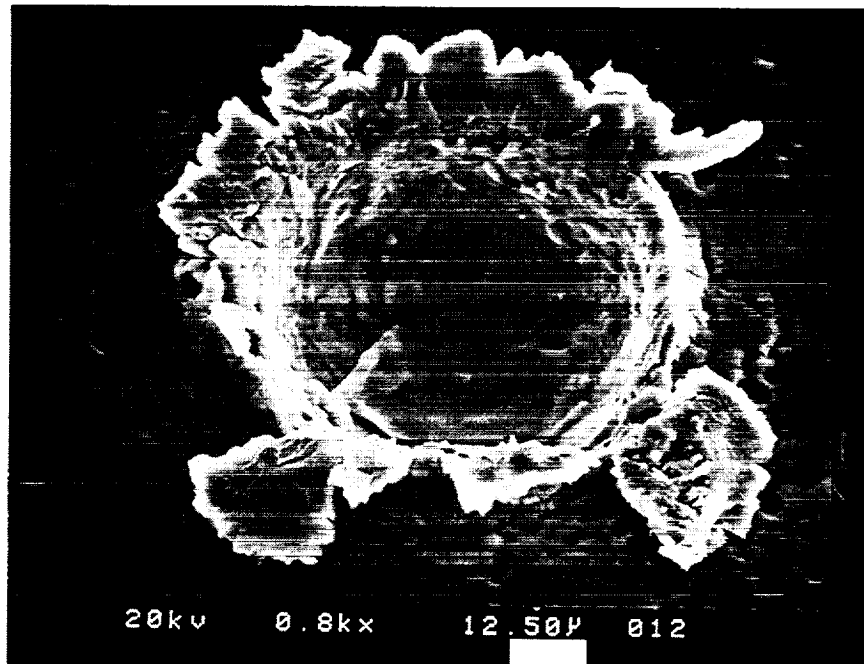
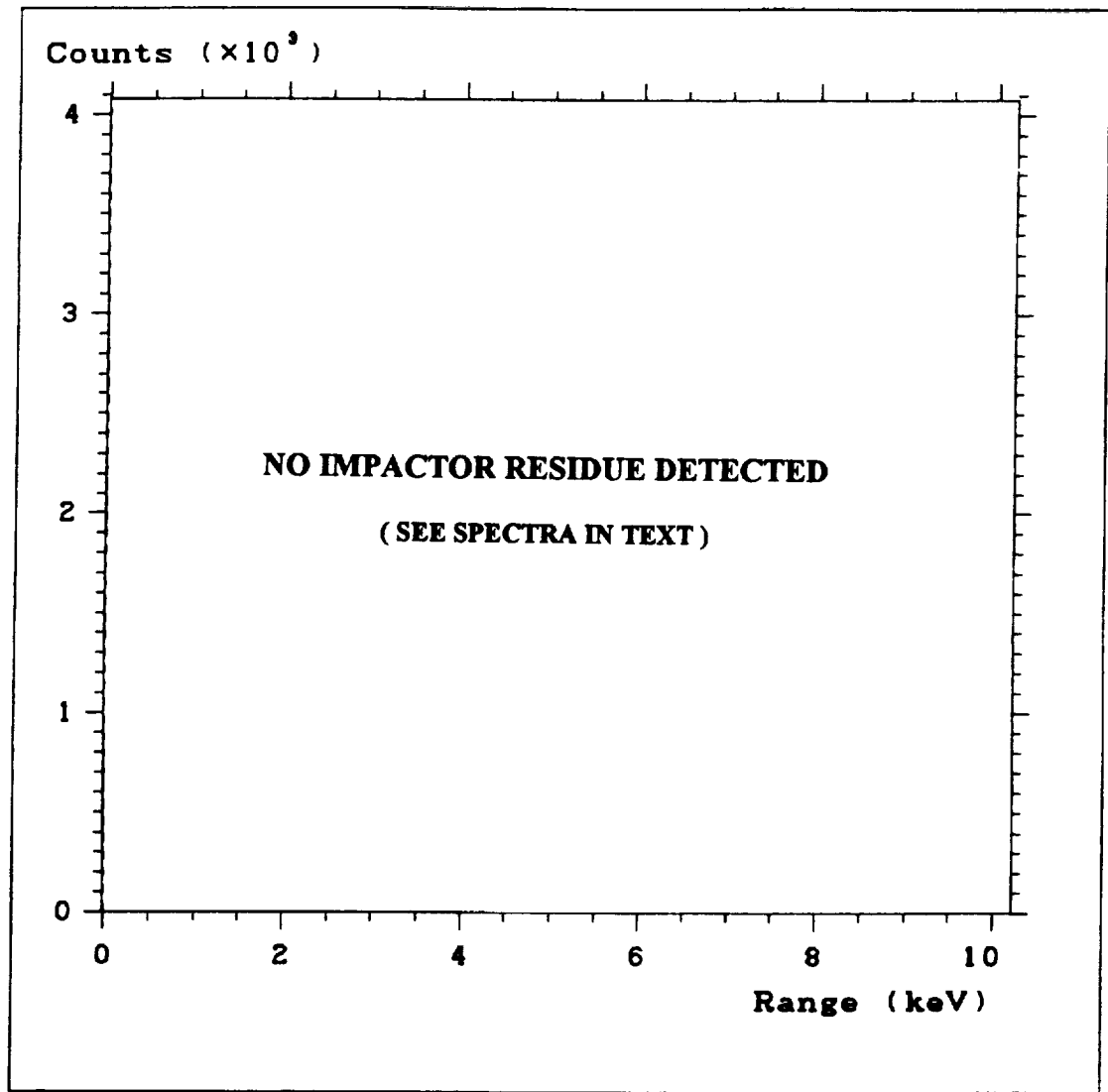






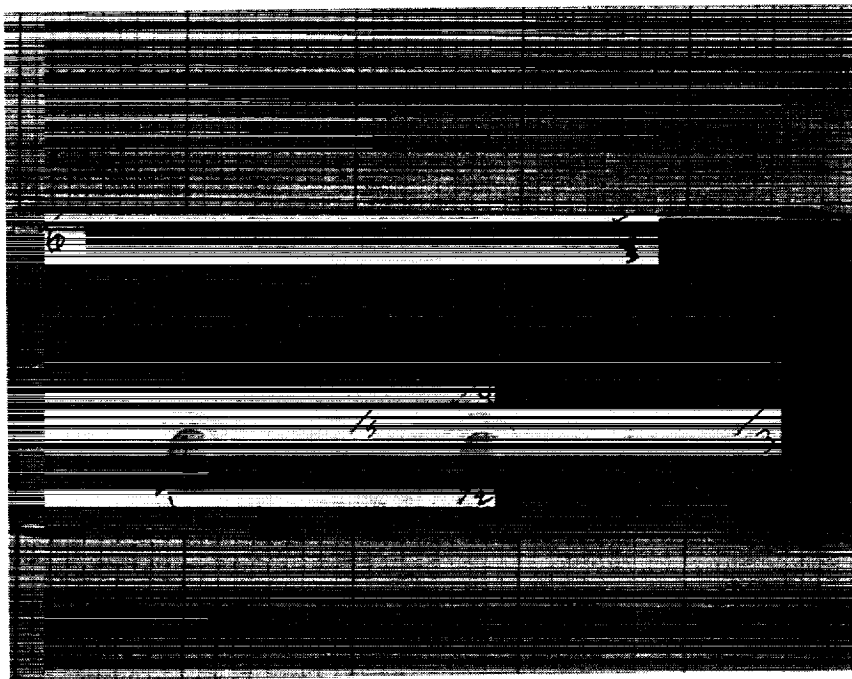


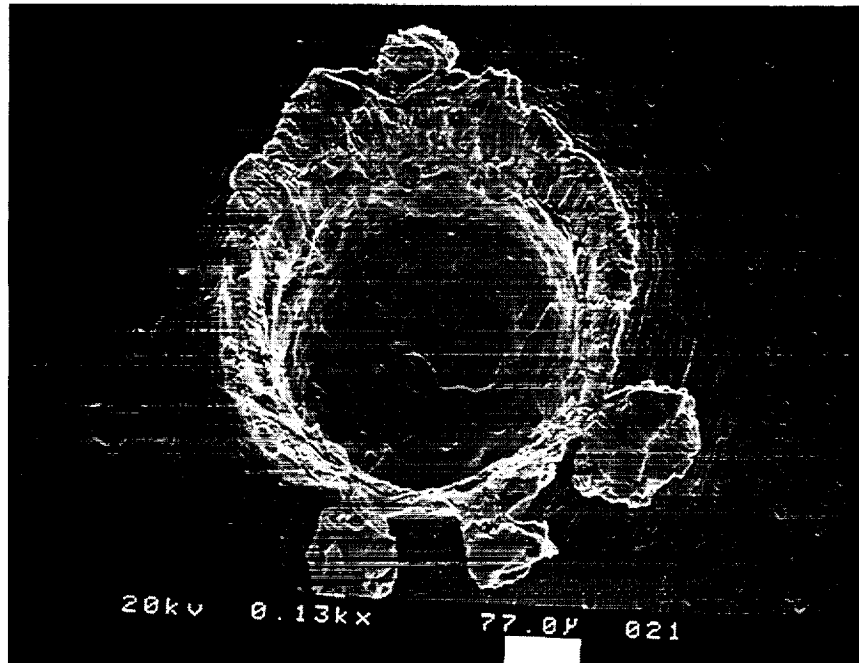
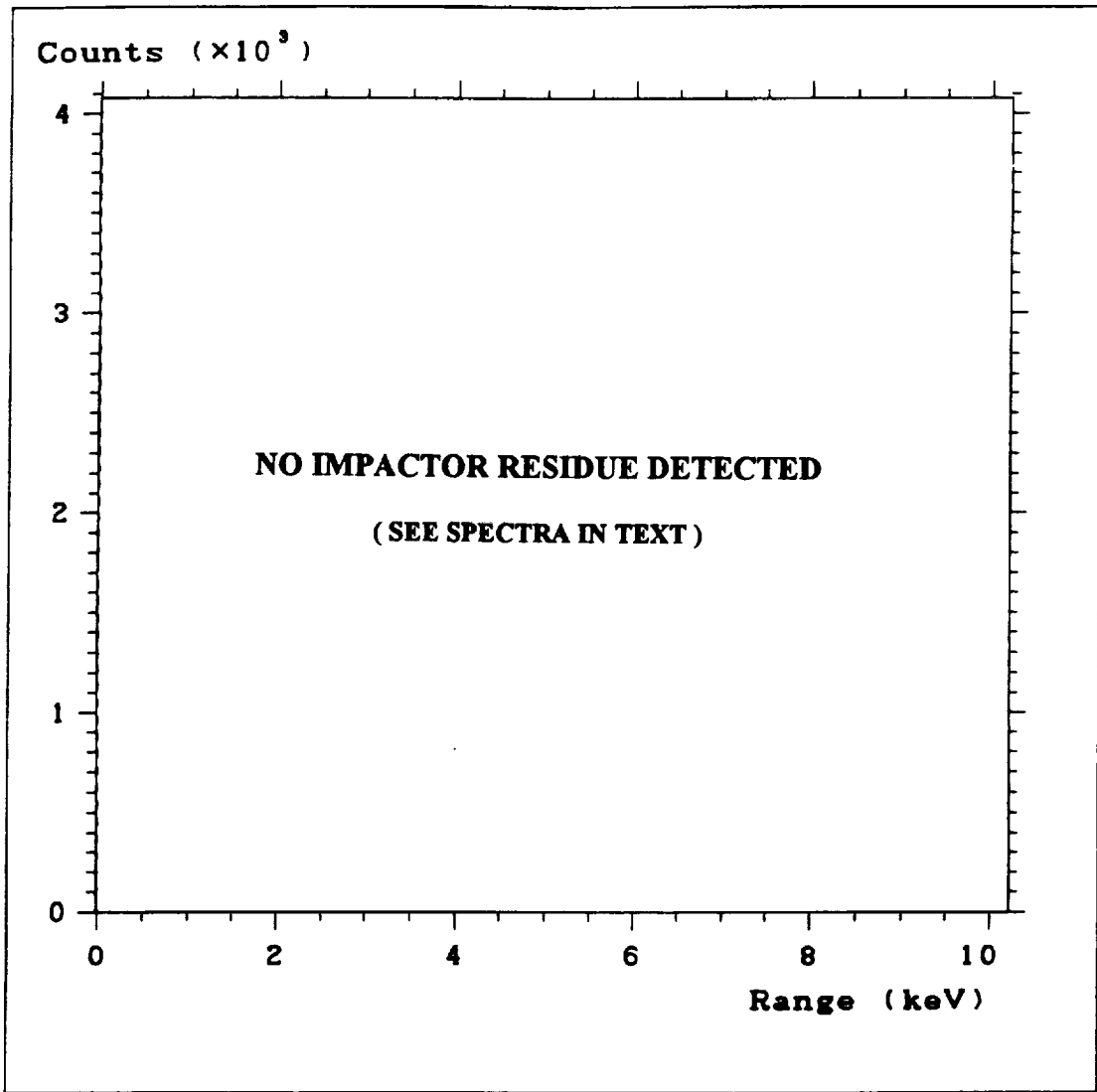


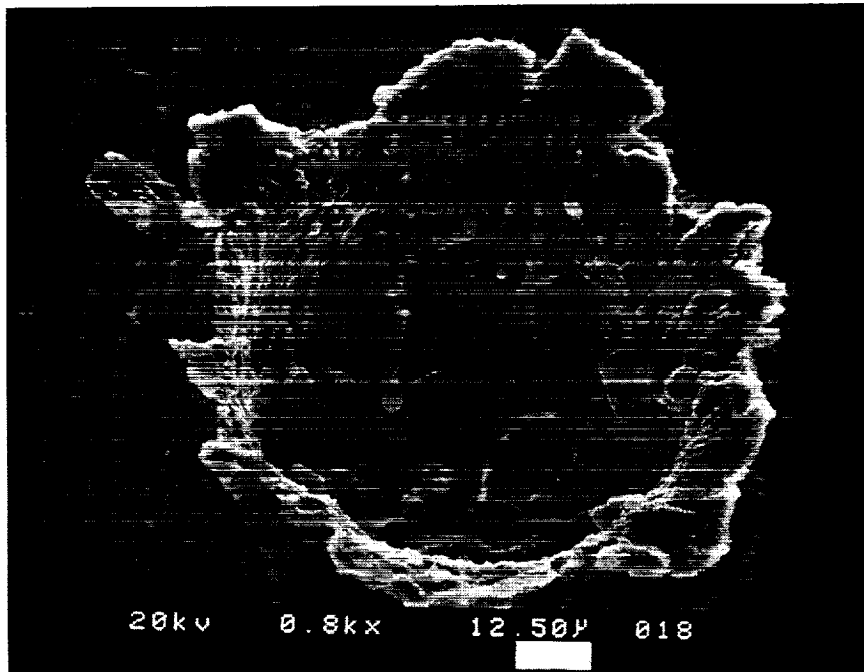
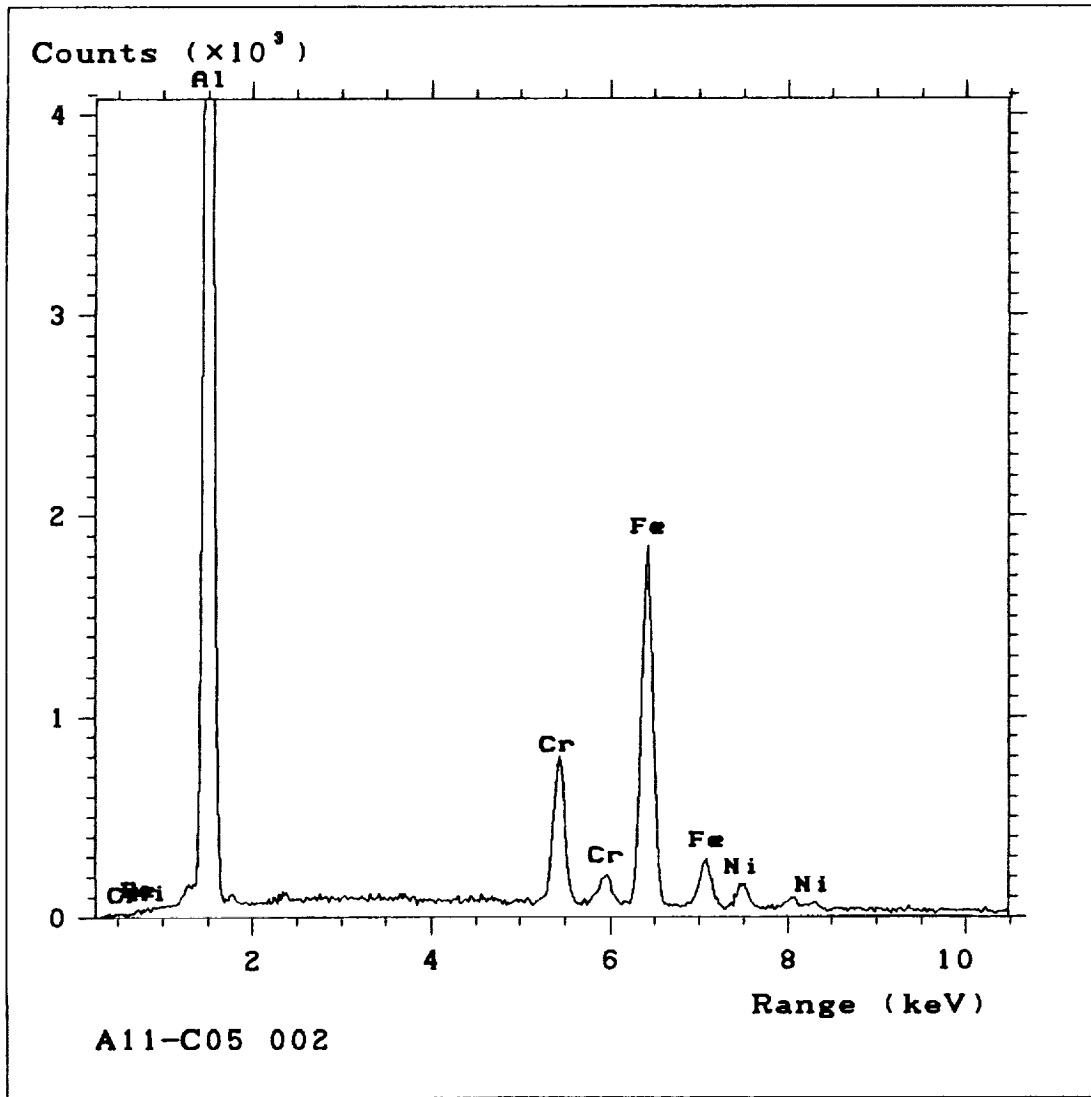


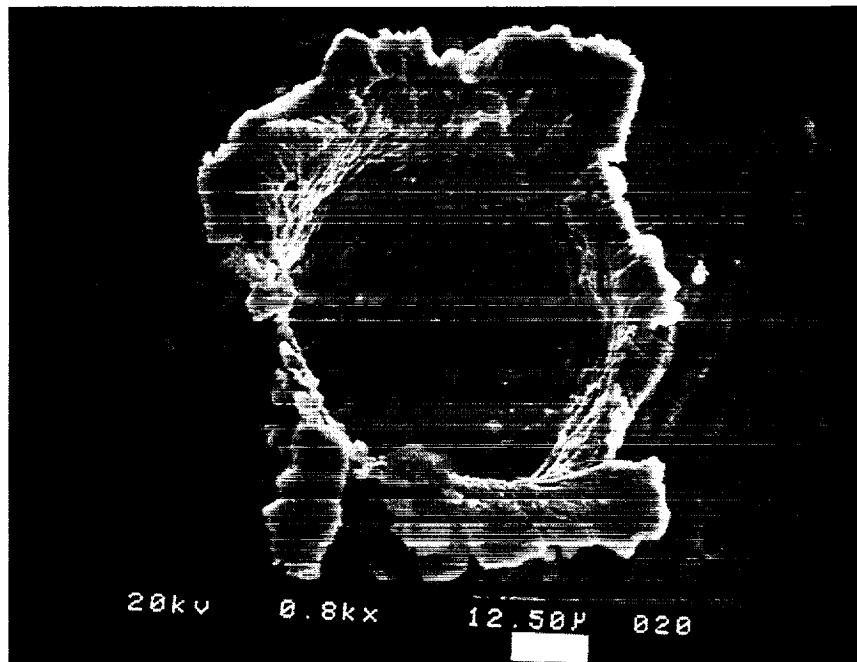
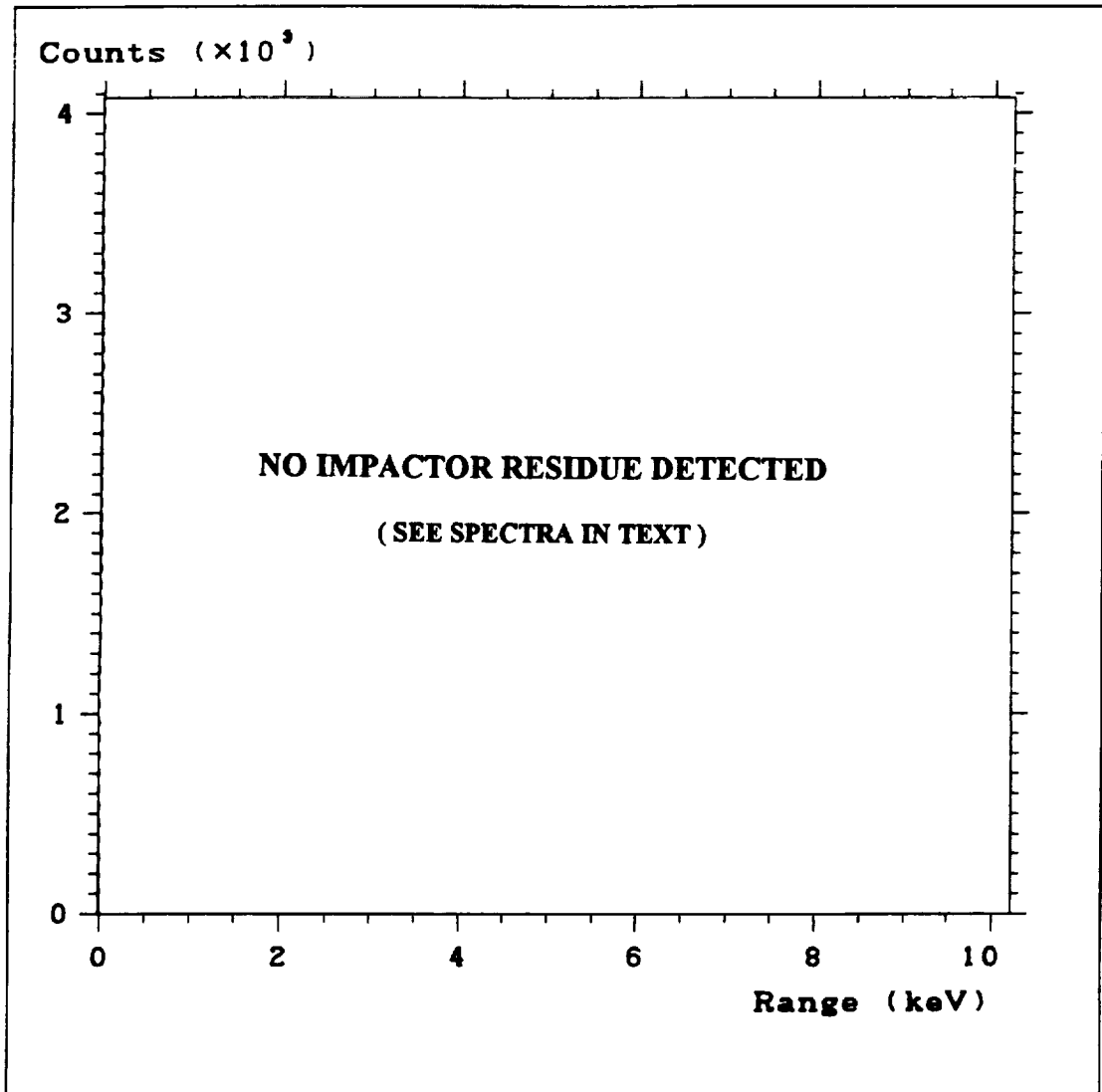
CLAMP NUMBER A11 C05

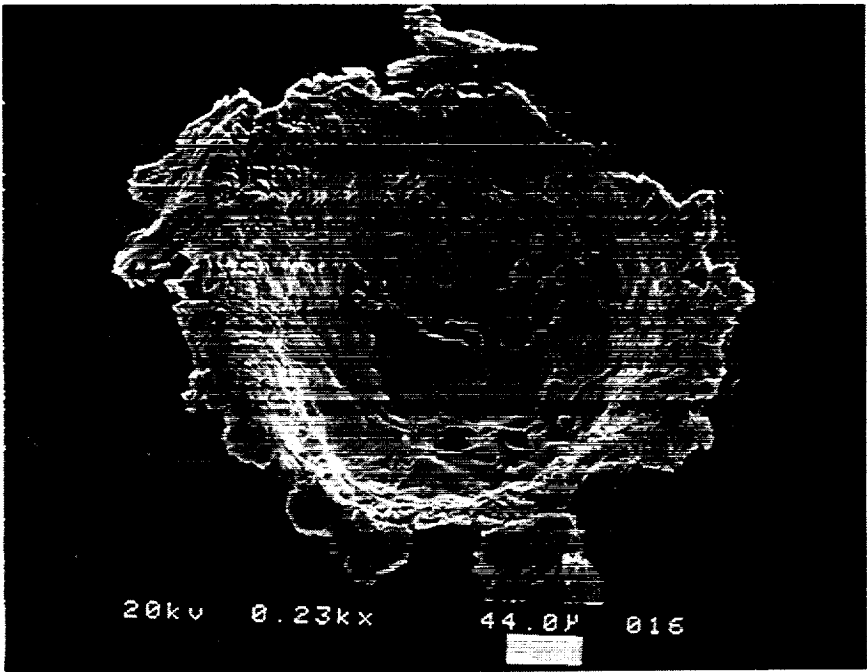
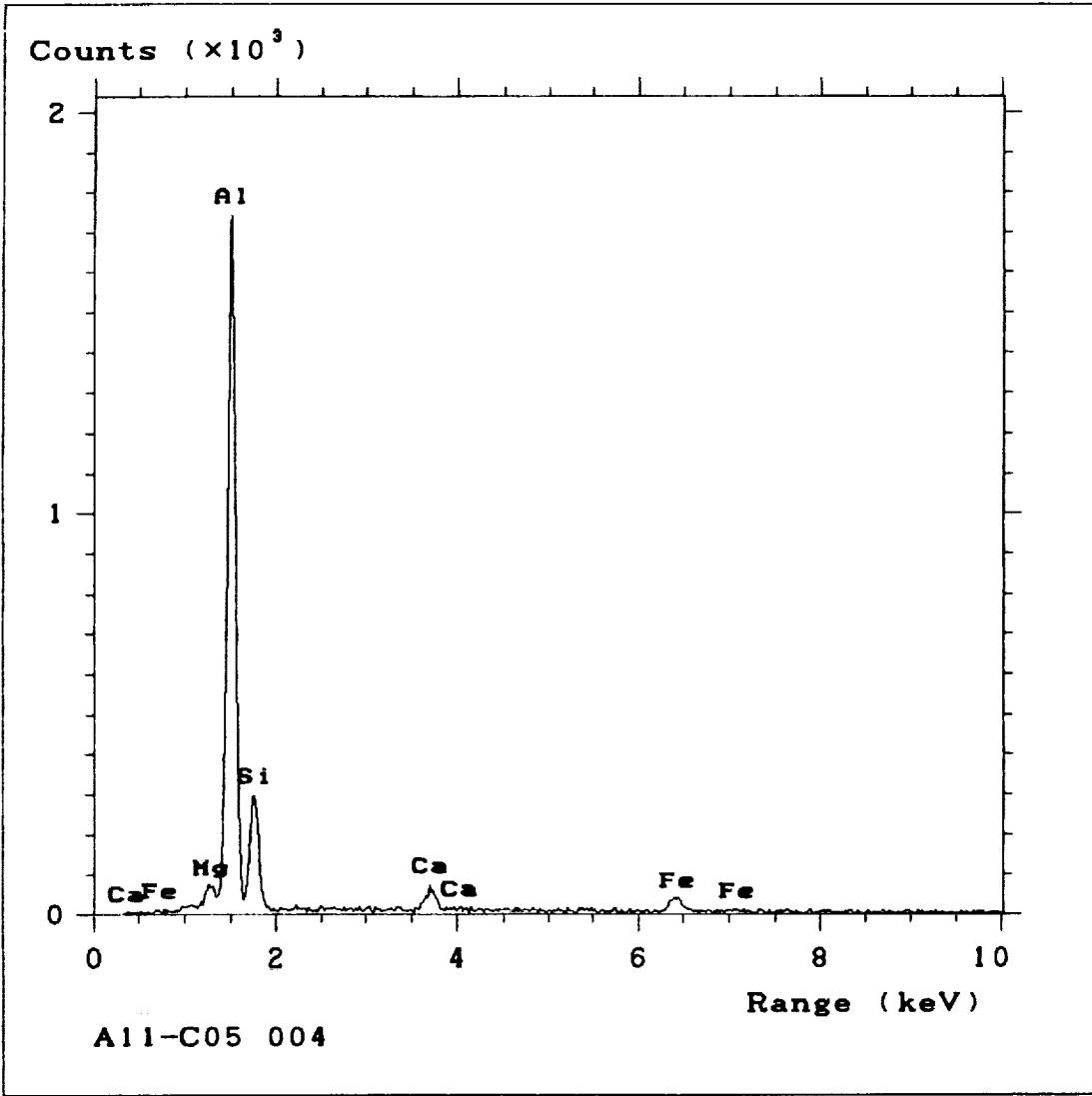
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	400	Unknown
002	120	Fe, Ni, Cr
003	100	Unknown
004	250	Trace
005	150	Unknown
006	120	Mg, Si, Ca, Fe

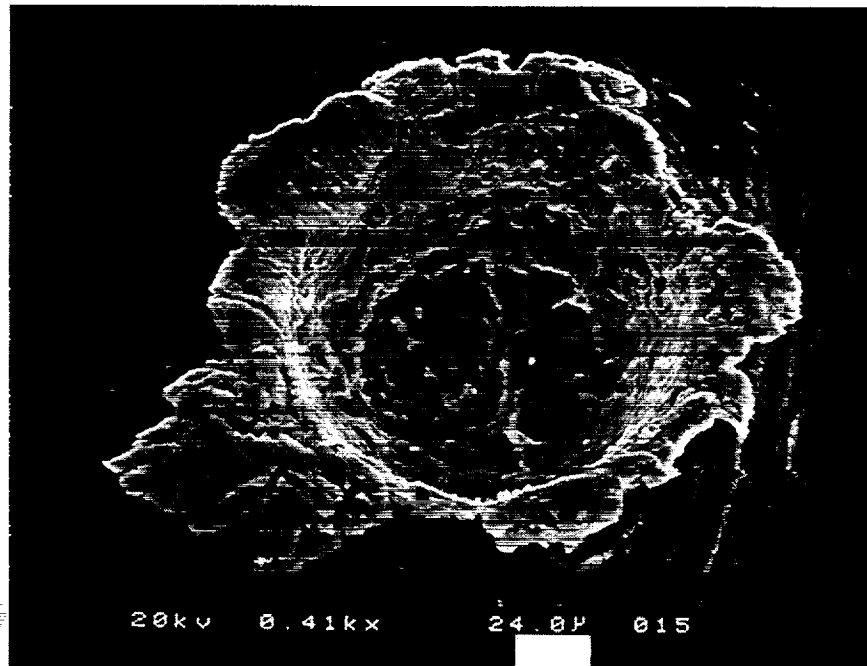
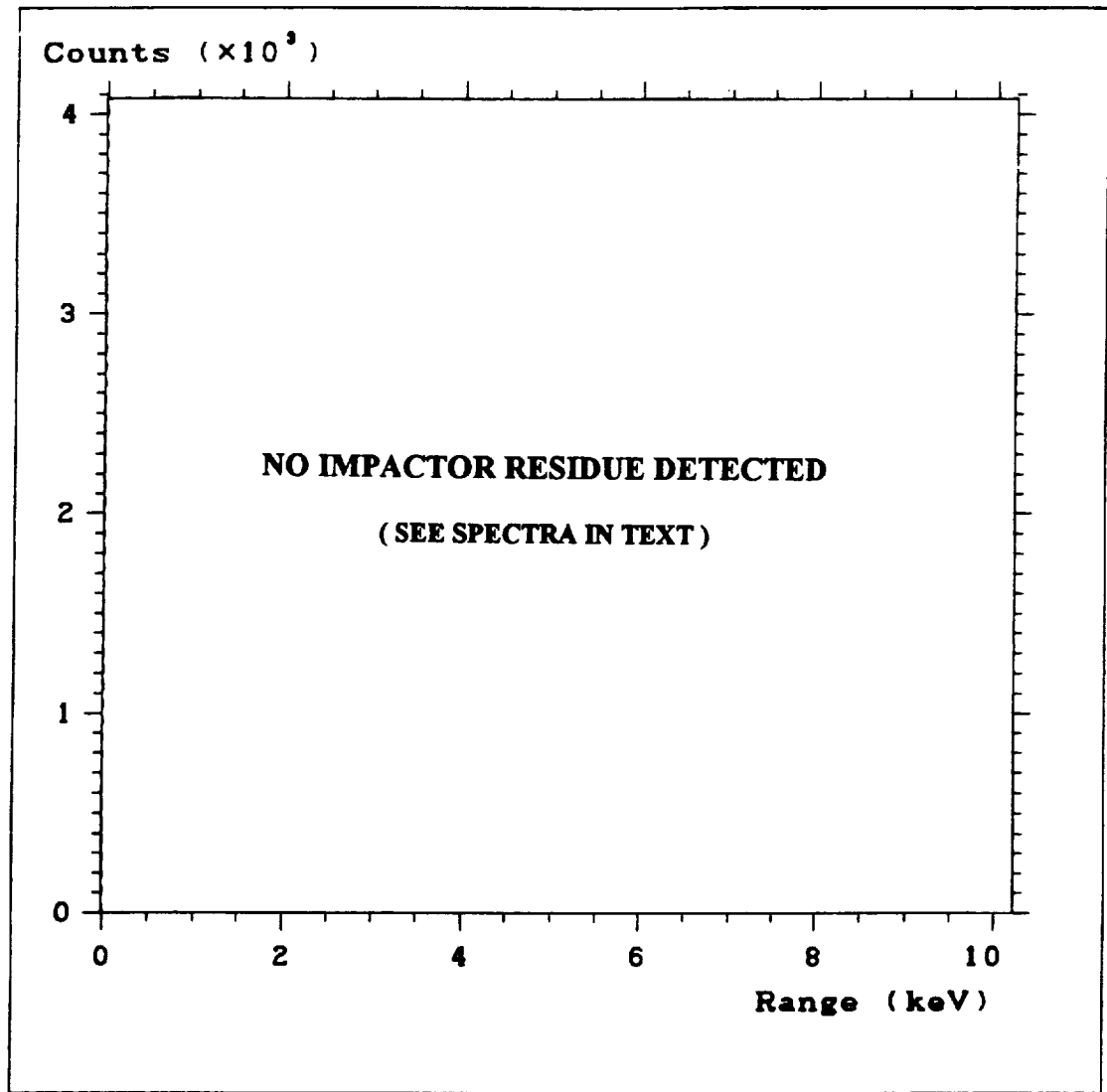


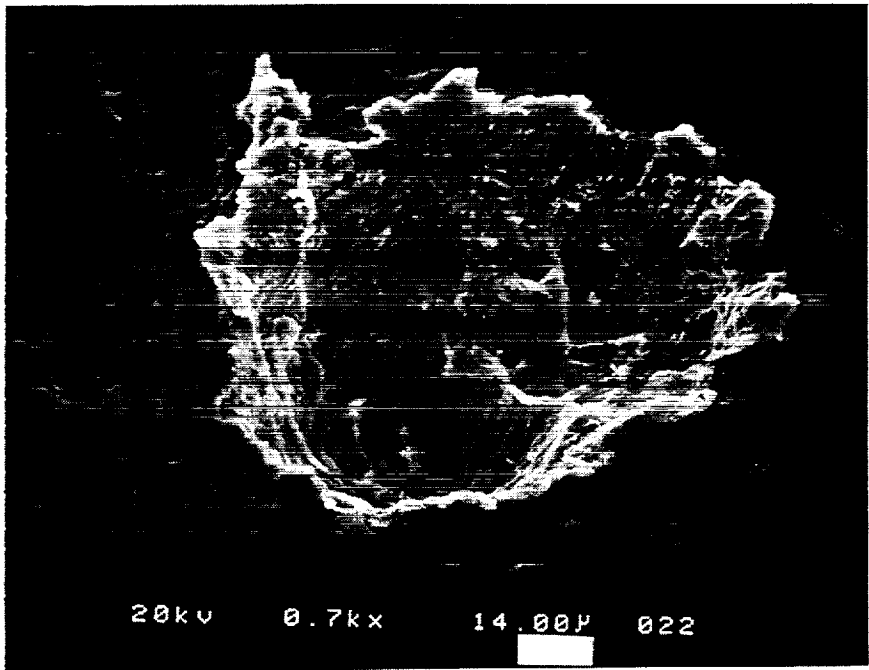
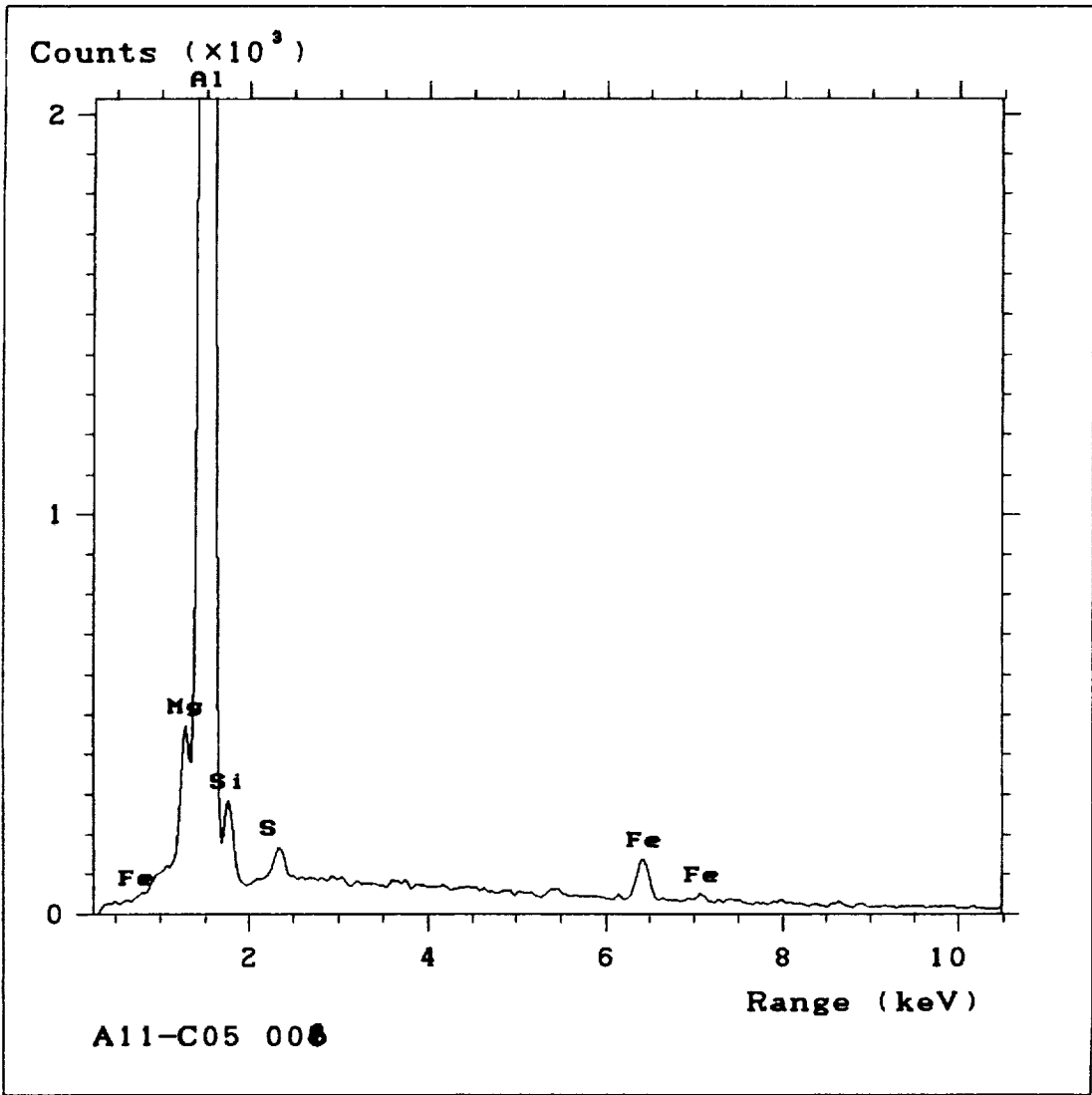






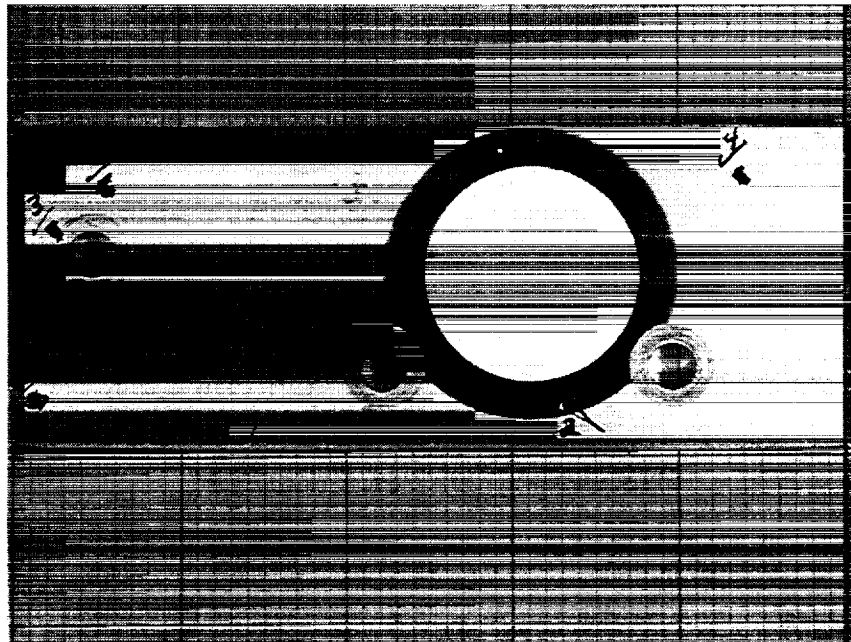


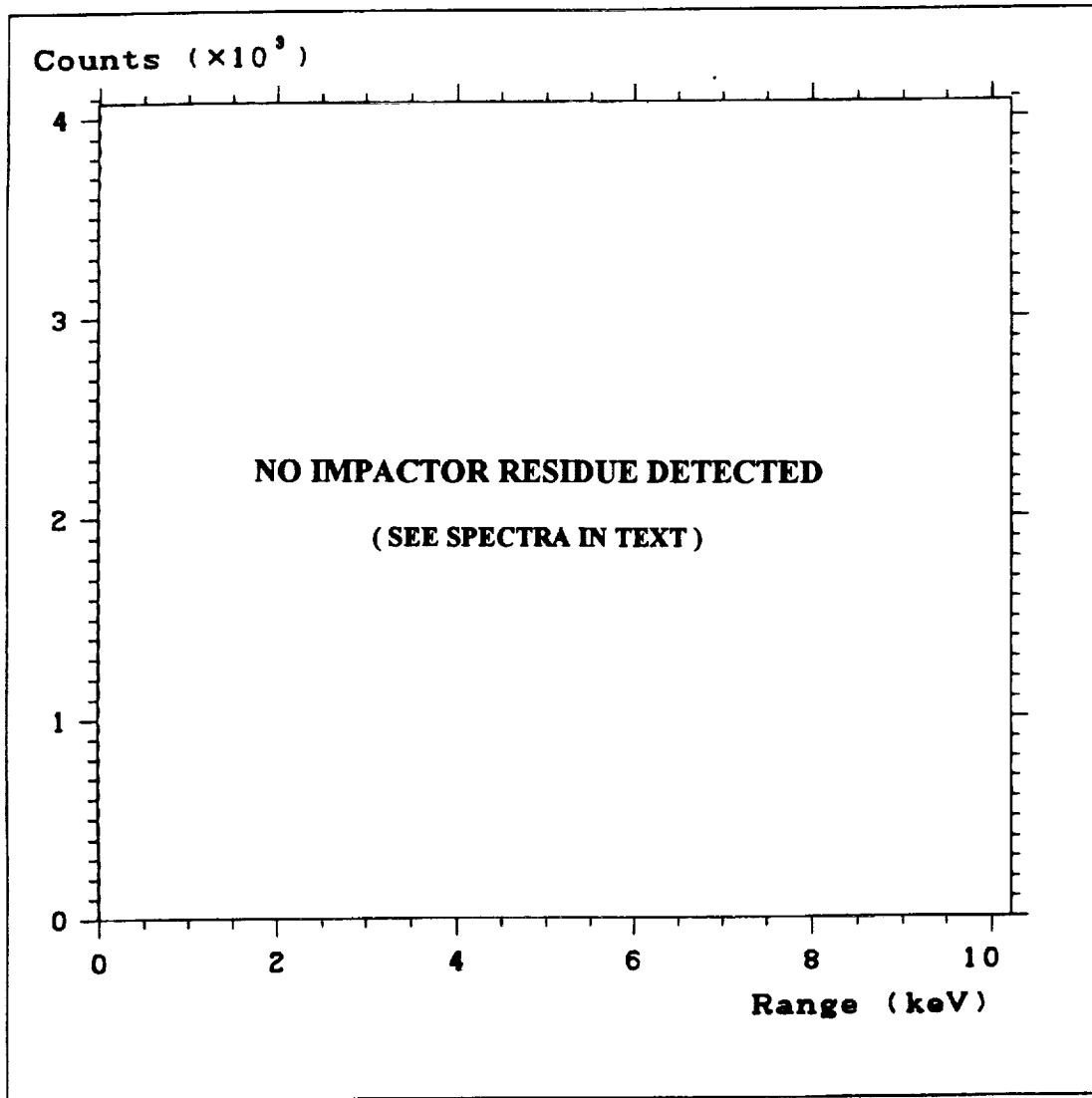


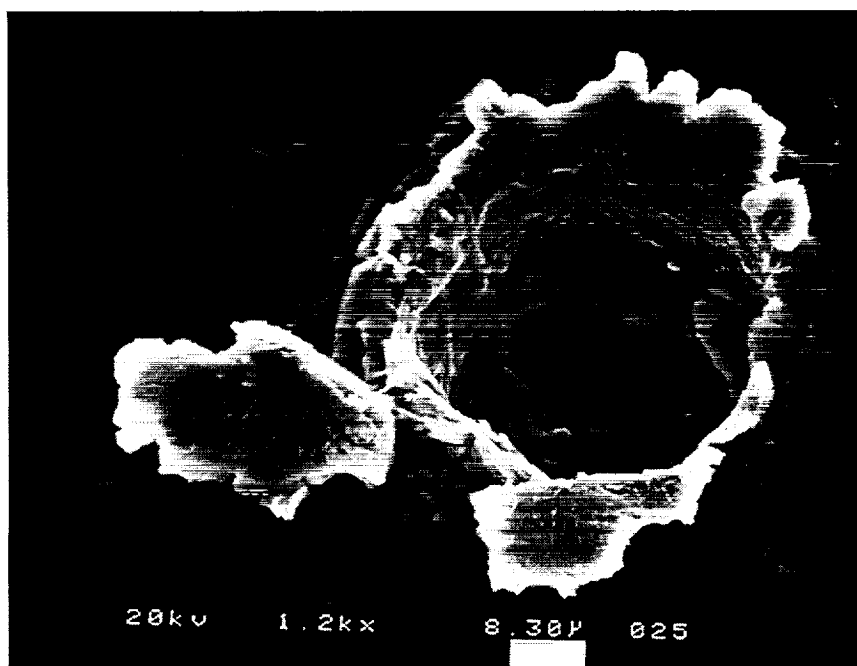
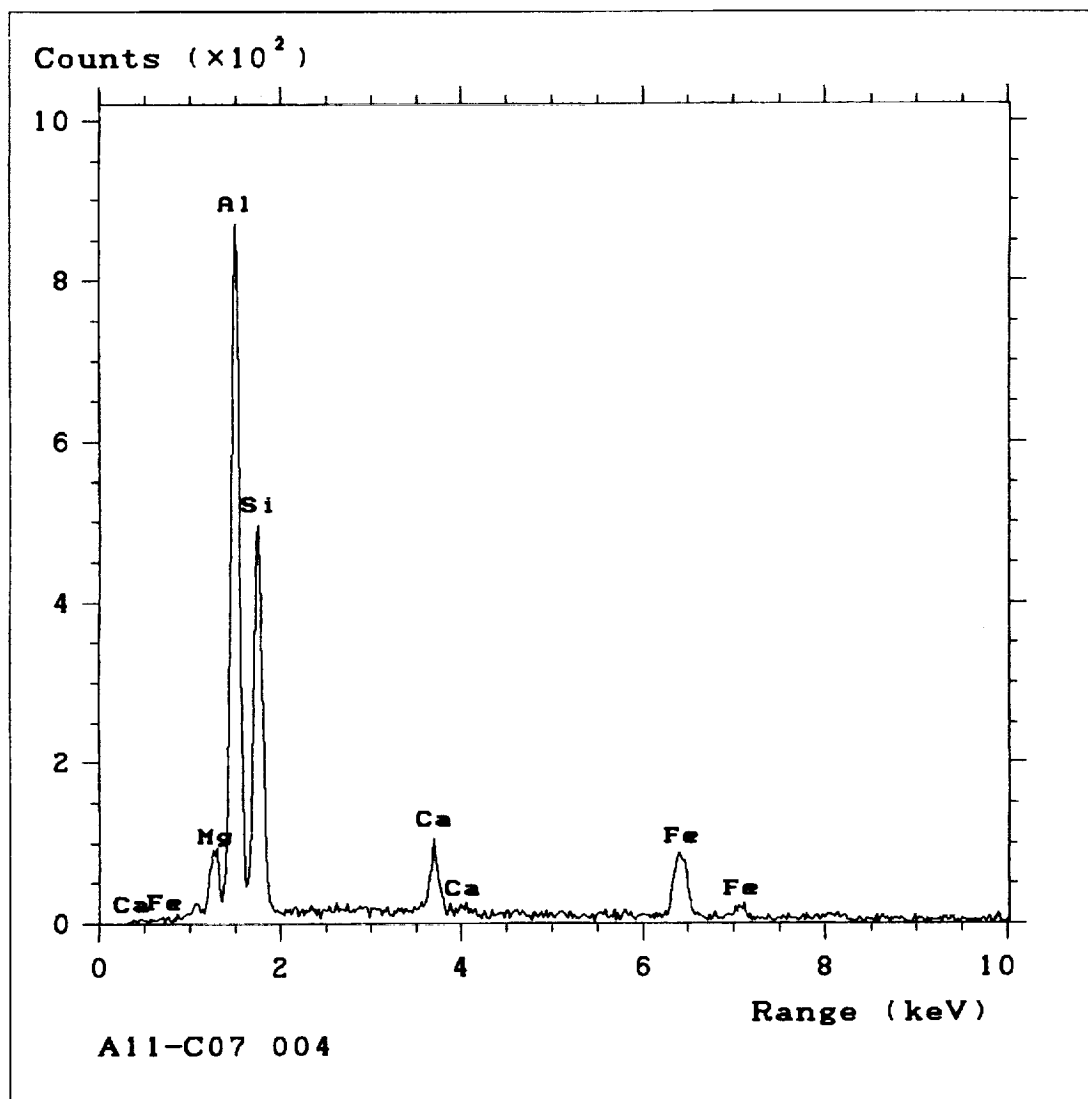


CLAMP NUMBER A11 CO7

<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	550	Paint Patch
002	100	Paint Patch
003	150	Unknown
004	60	Si, Mg, Ca, Fe

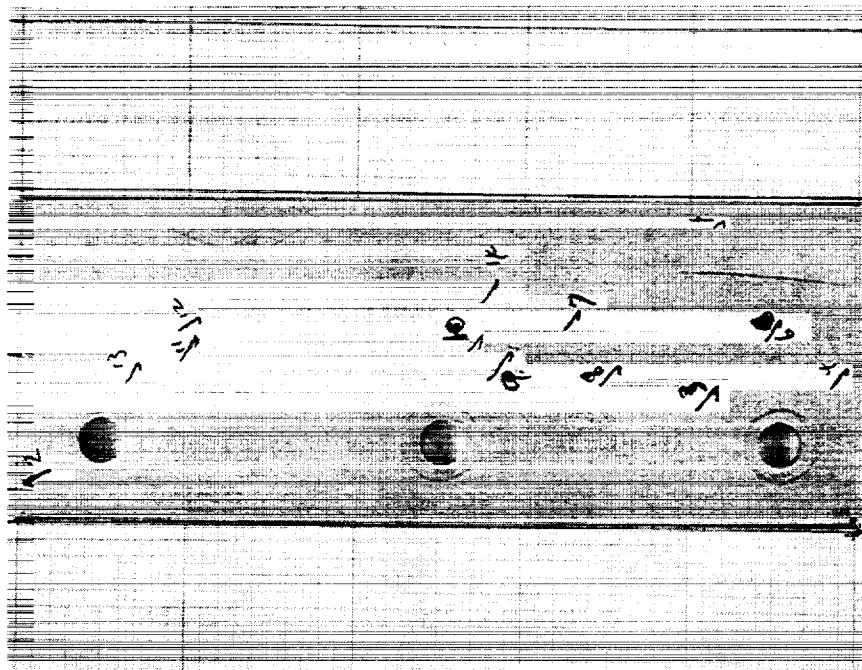


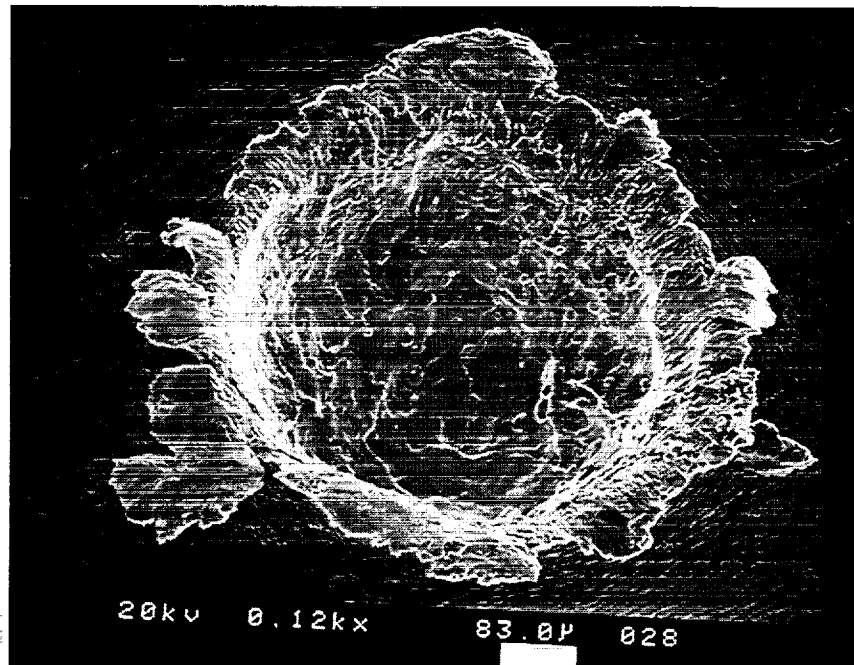
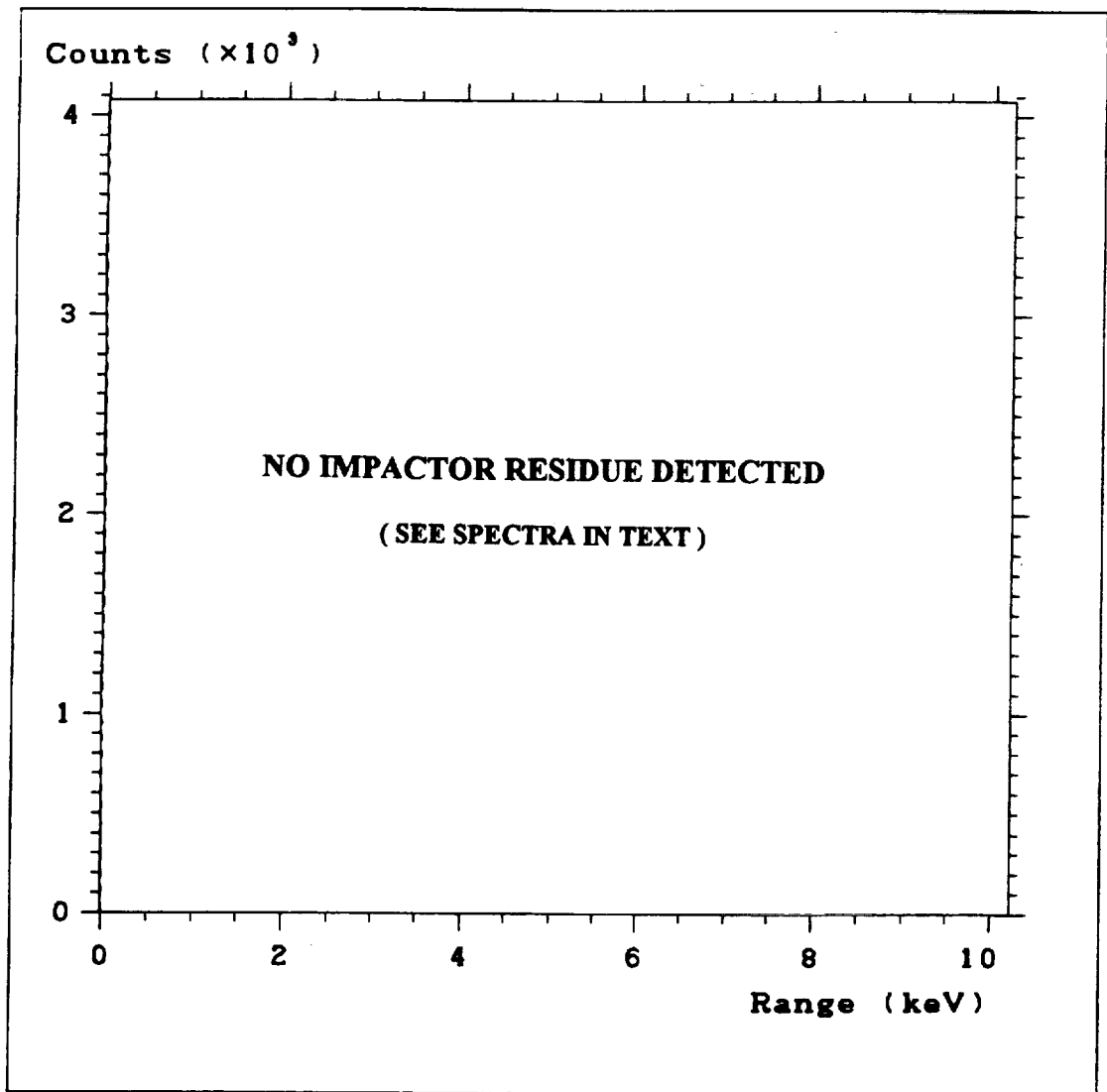


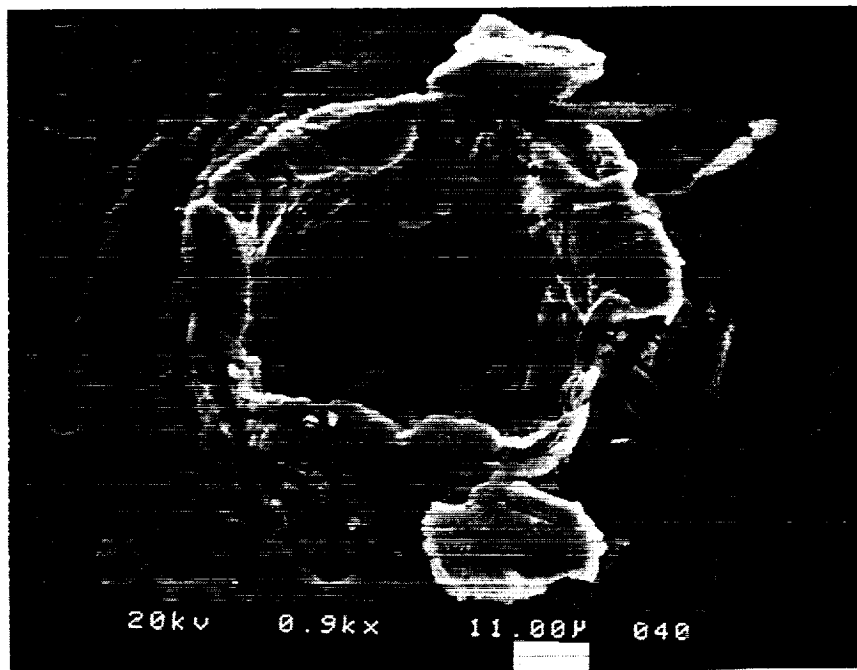
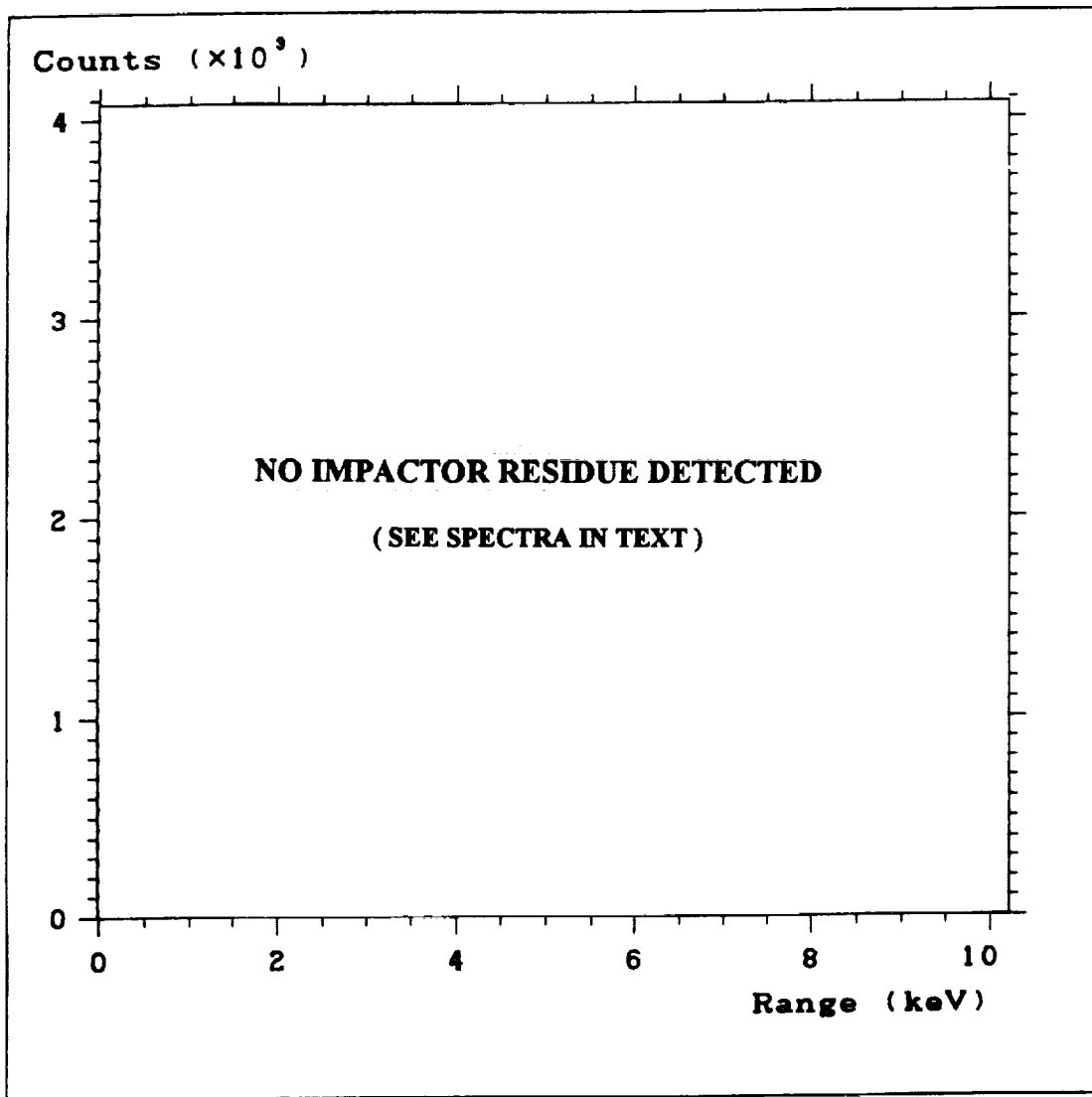


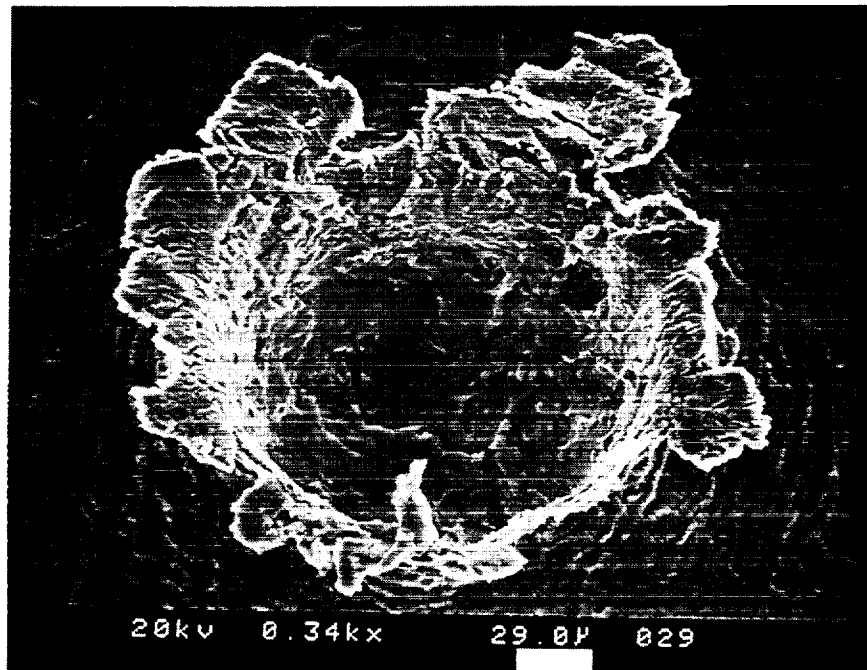
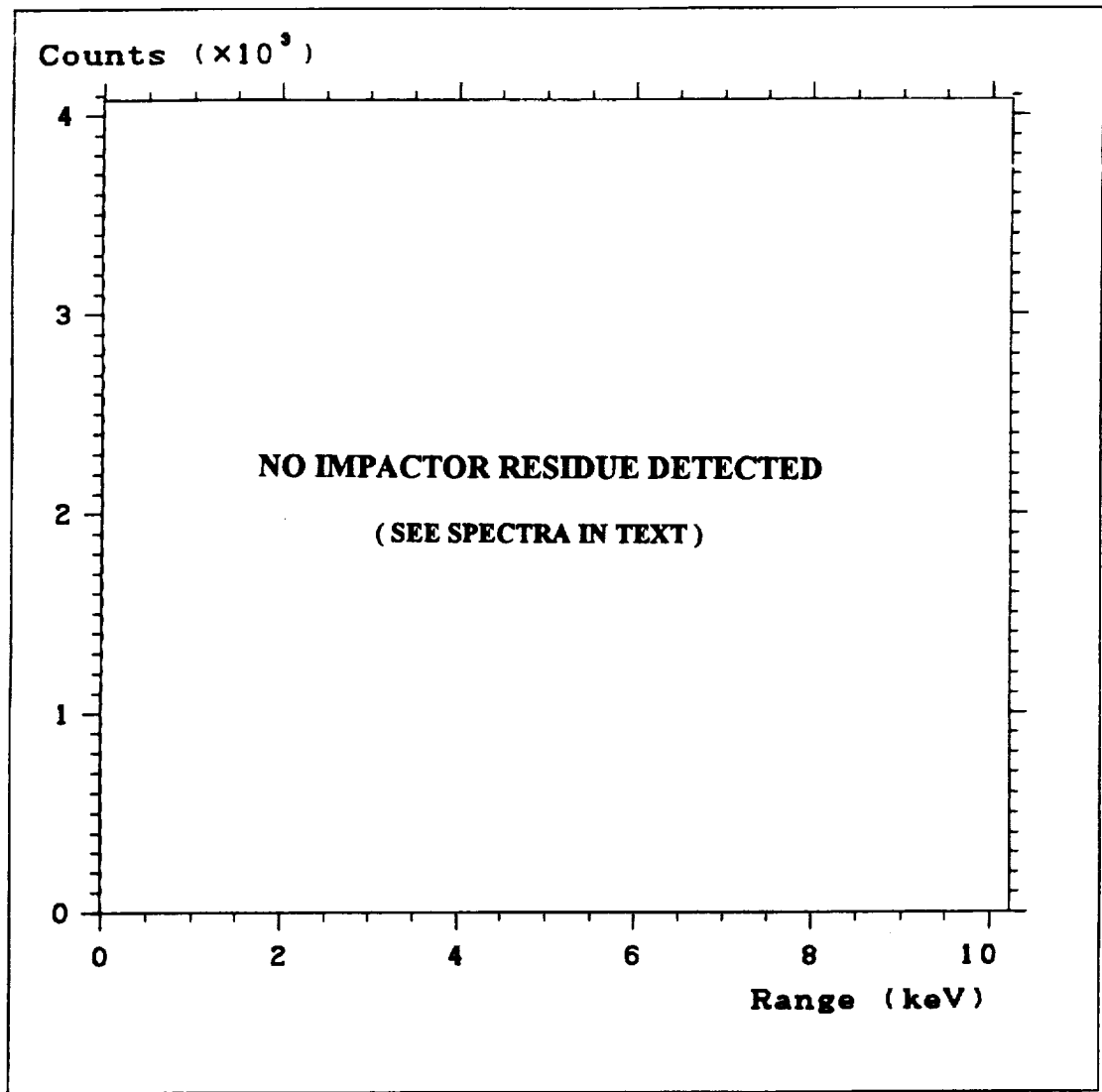
CLAMP NUMBER A11 C08

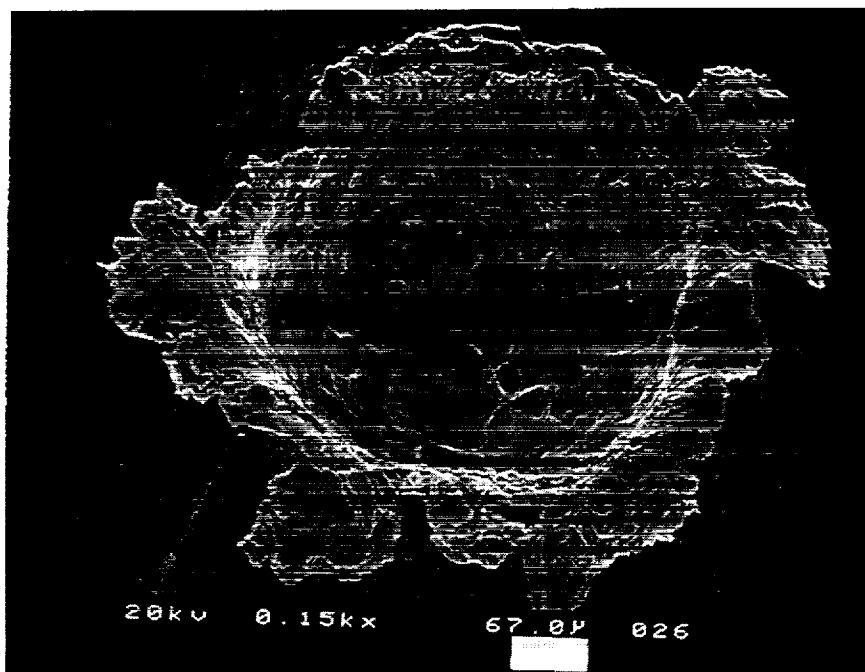
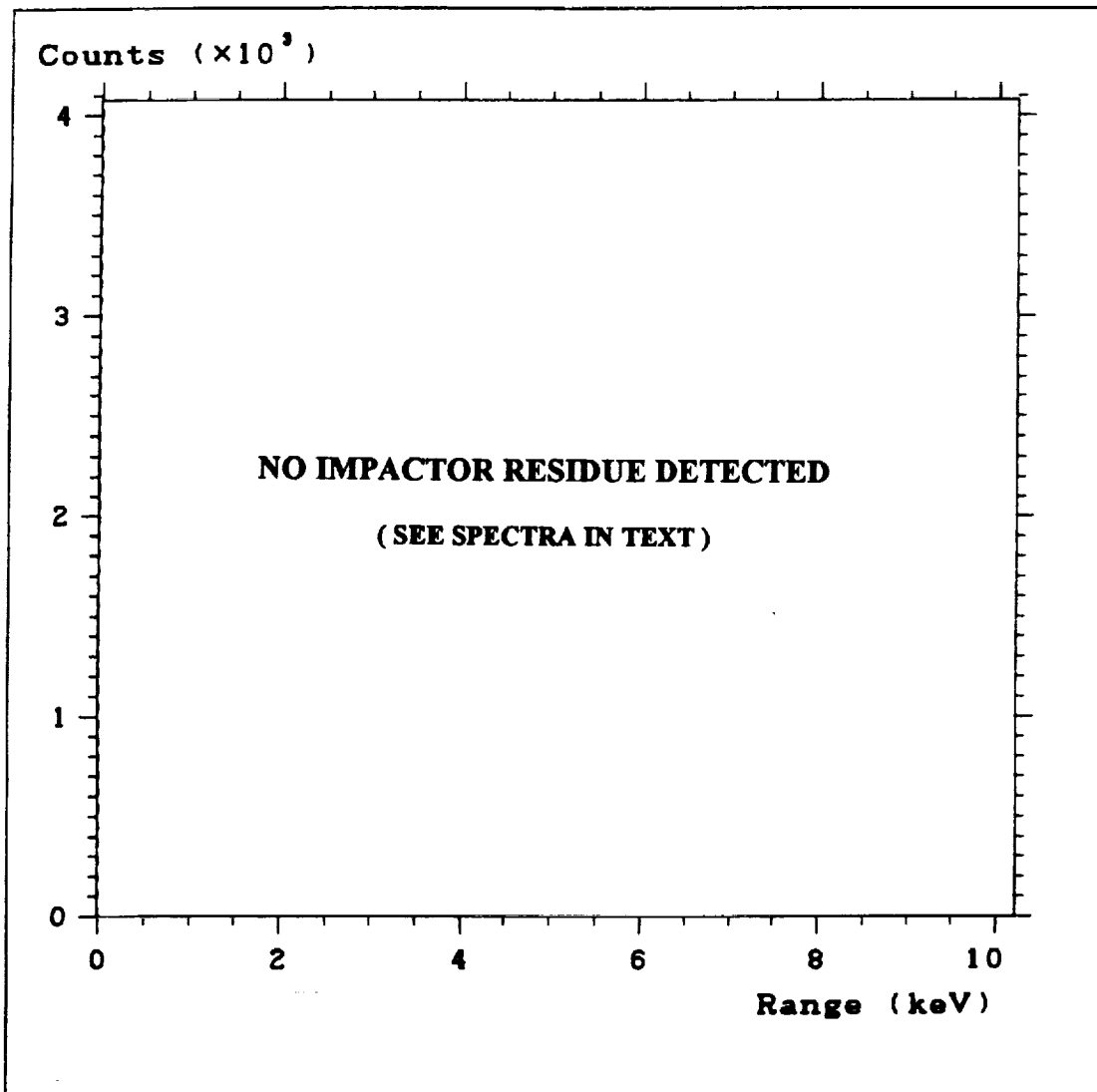
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	600	Unknown
002	60	Unknown
003	200	Unknown
004	500	Unknown
005	N/A	Clamp Flaw
006	40	Ti, Cl, Si, Zn
007	400	Si, Mg, Fe
008	300	Unknown
009	300	Unknown
010	100	Trace
011	60	Zn, Ti, Cl, Si, S
012	200	Unknown
013	80	Unknown
014	140	Trace

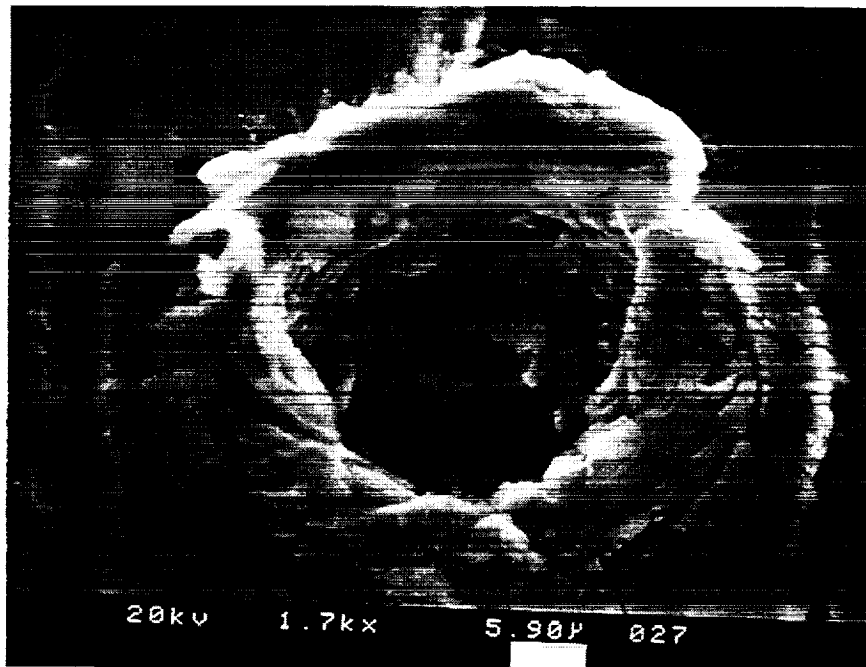
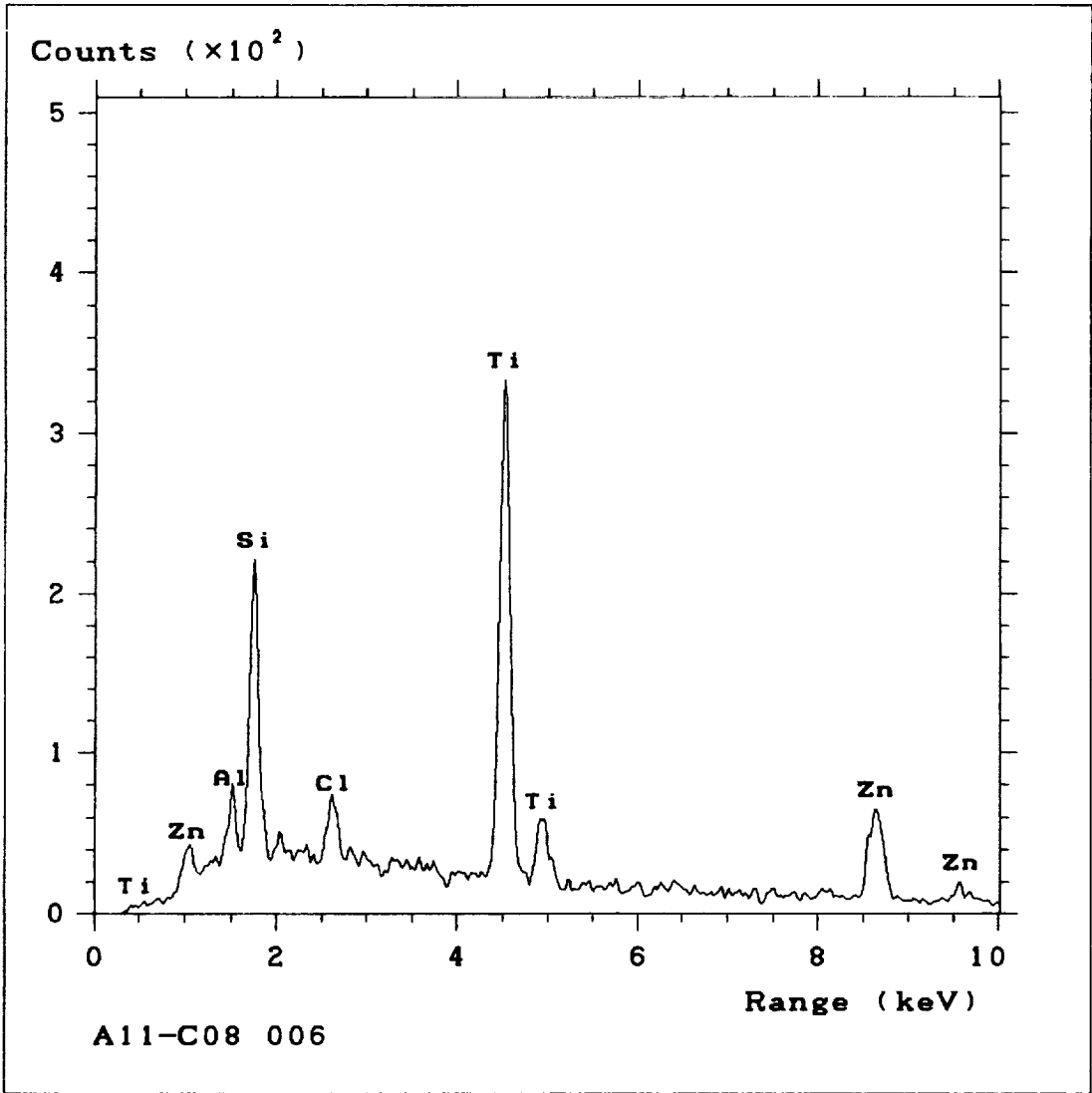


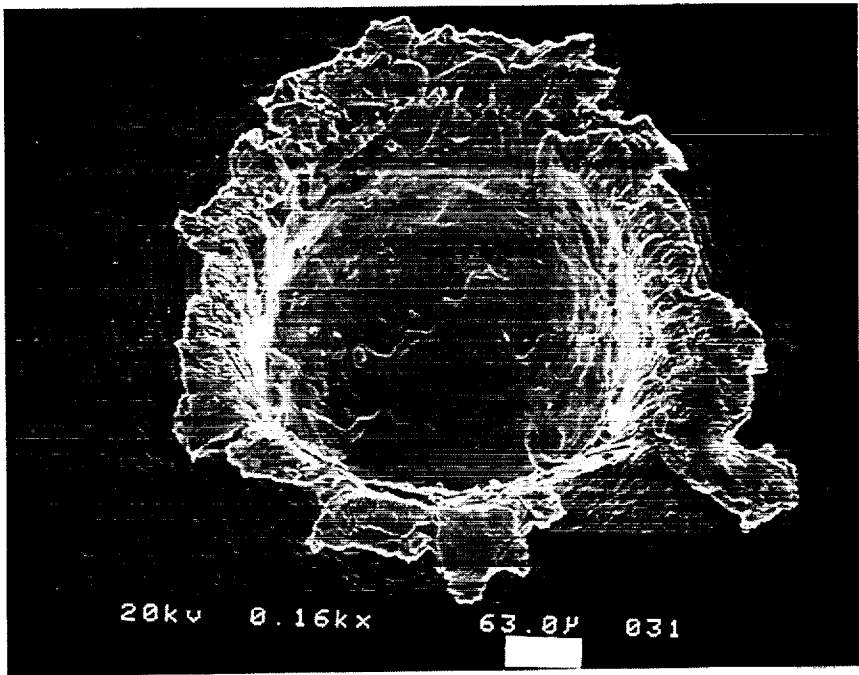
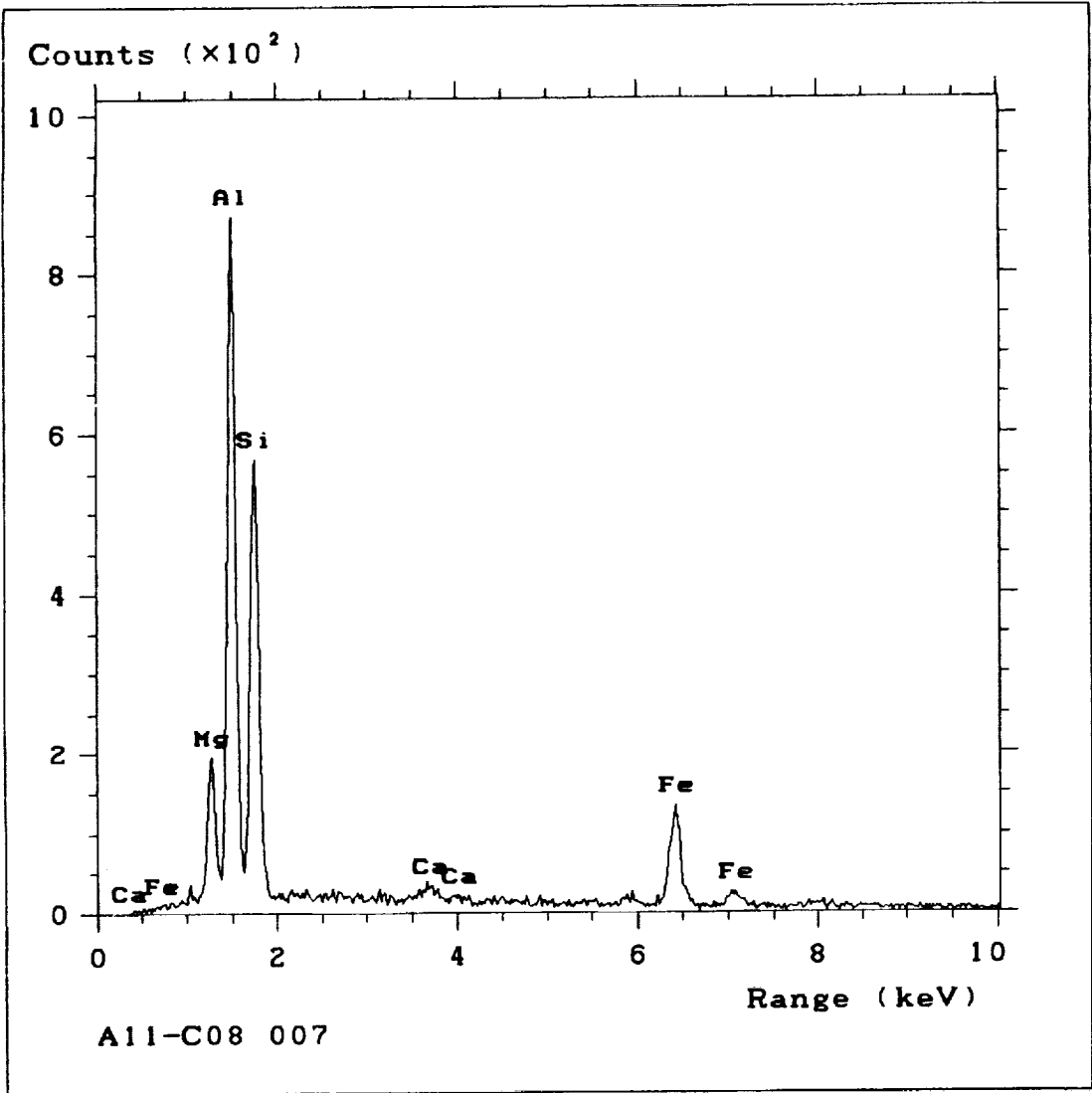


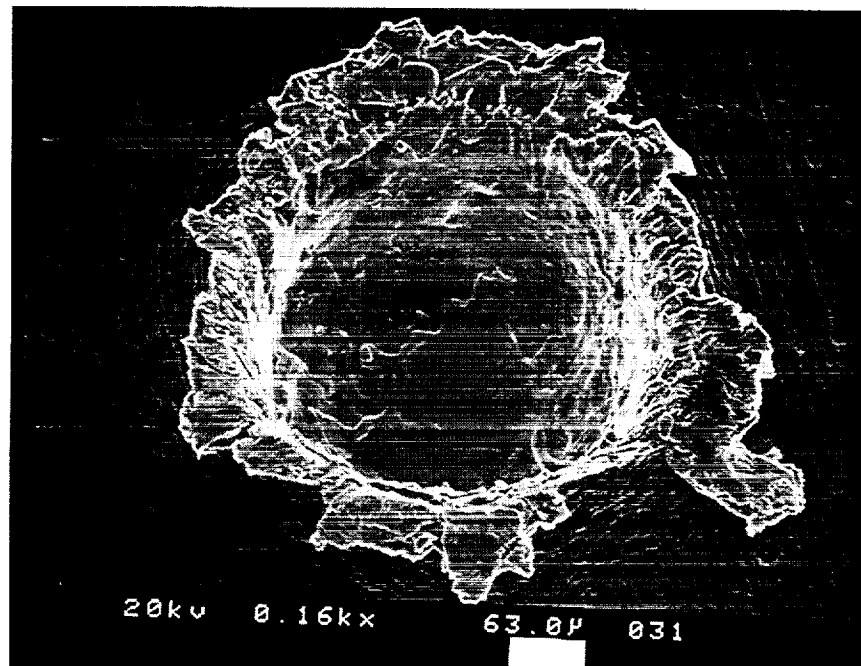
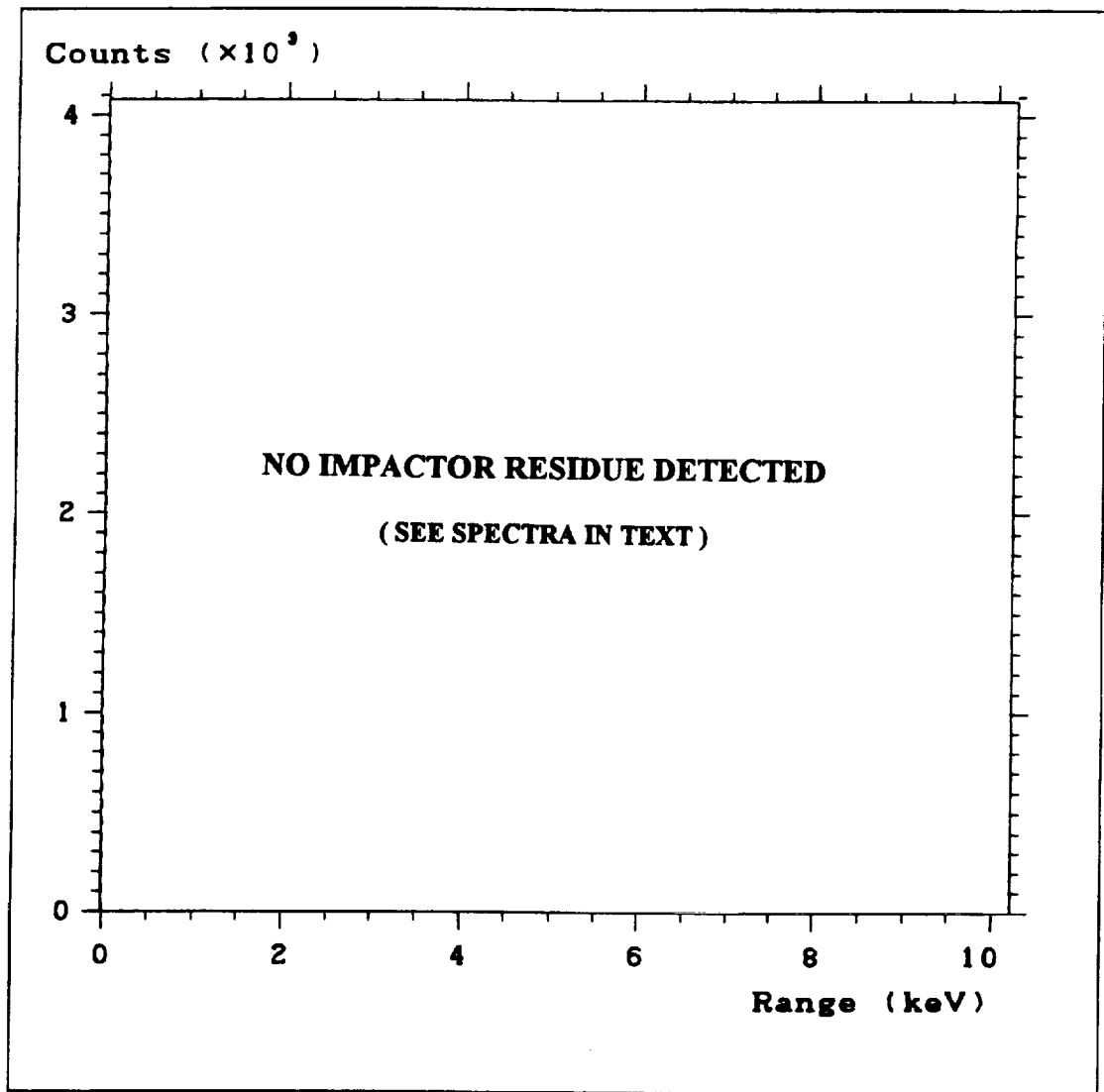


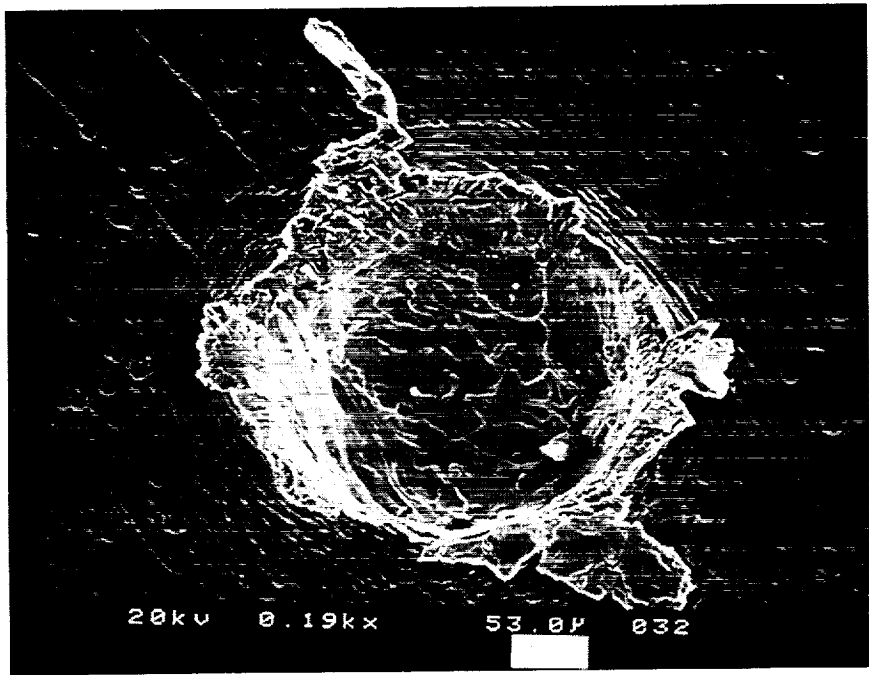
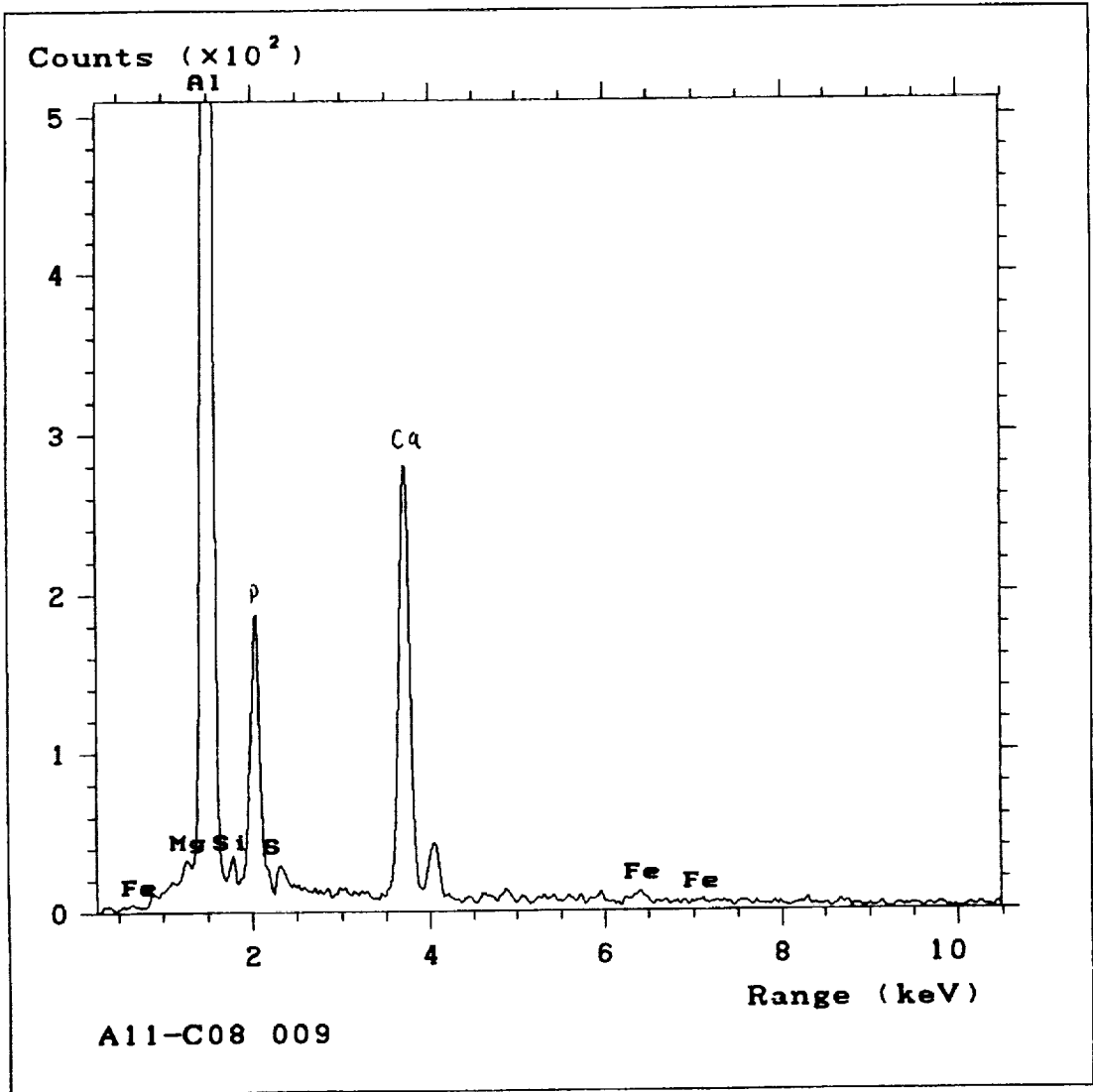


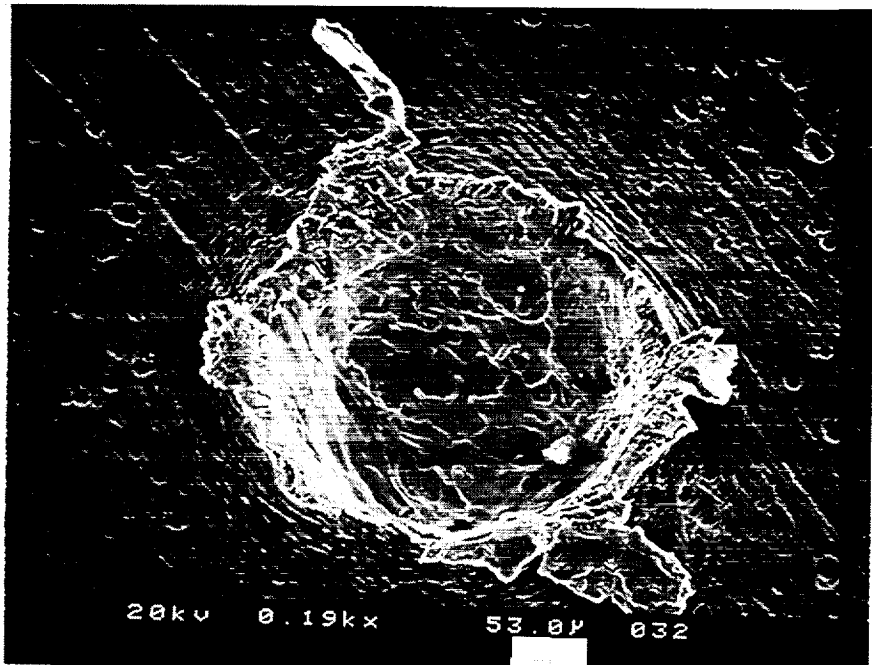
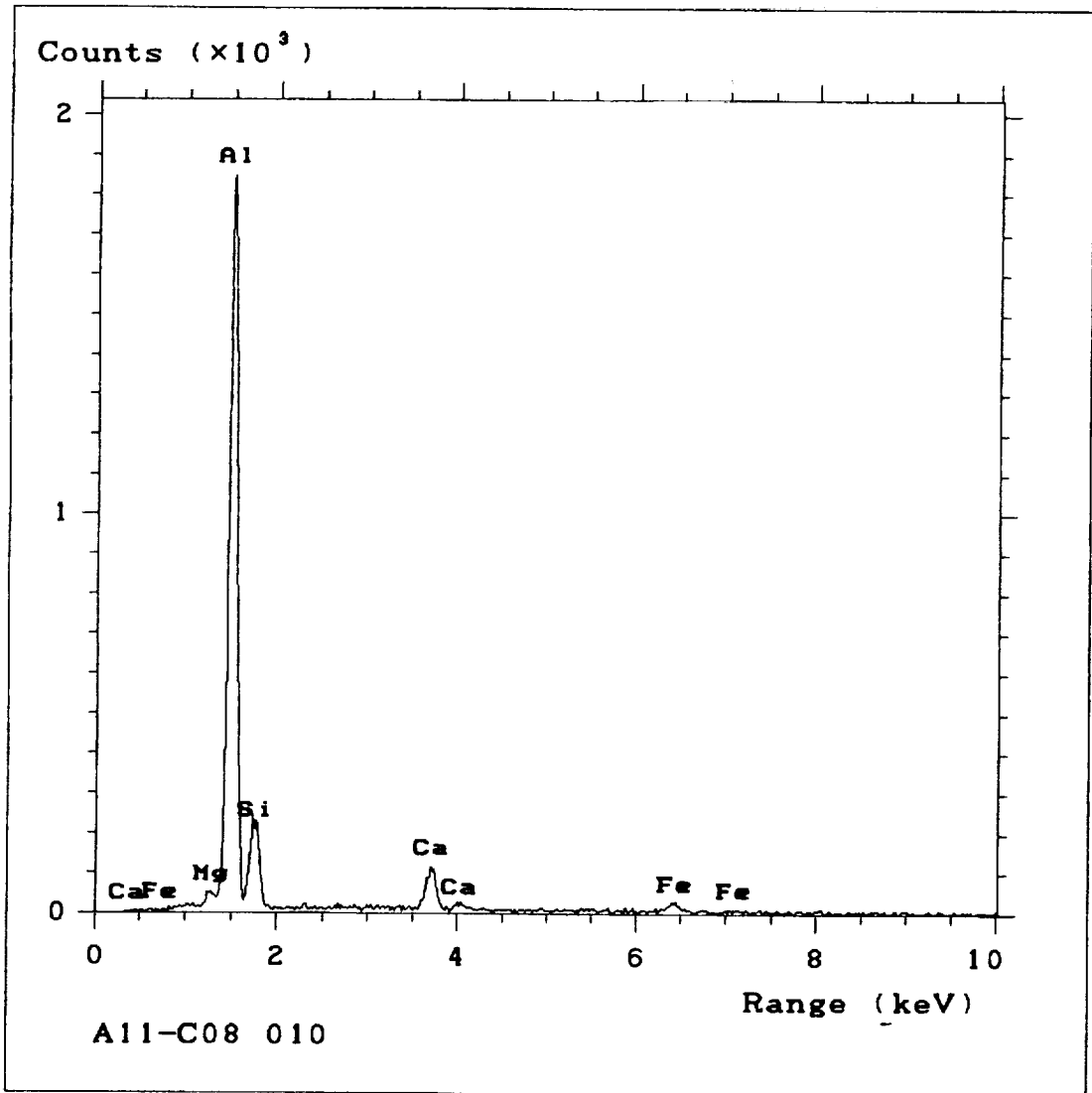


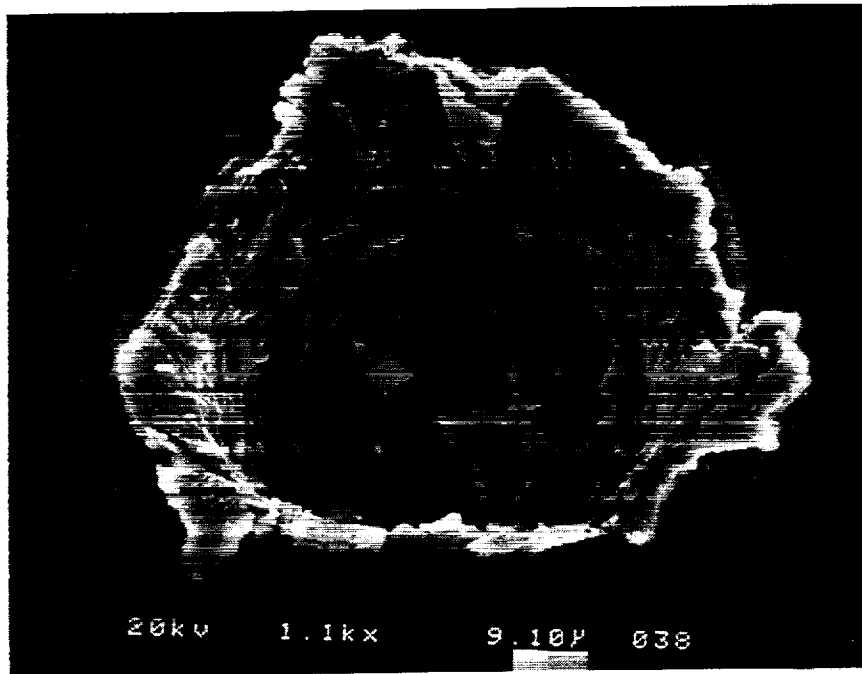
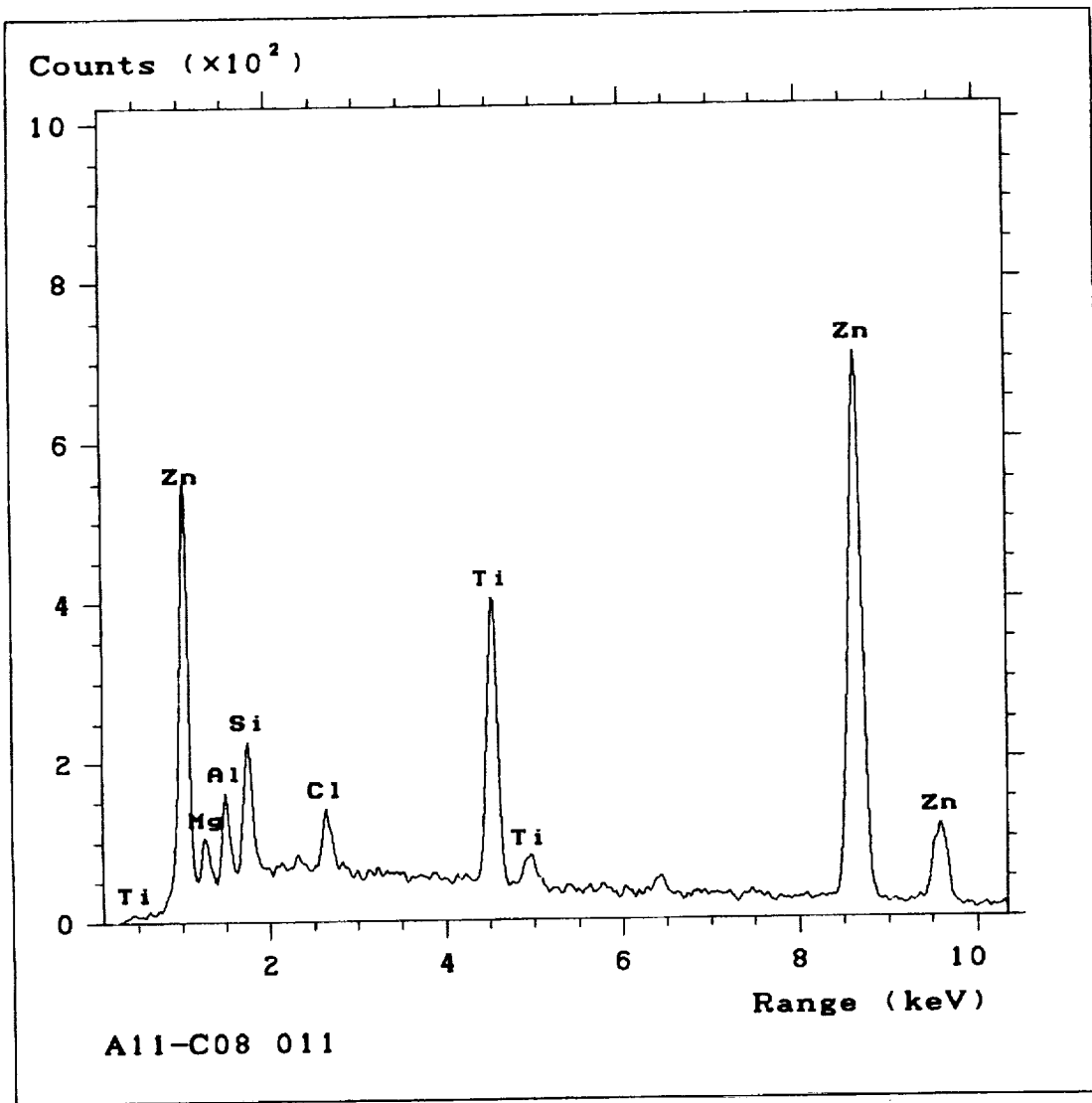


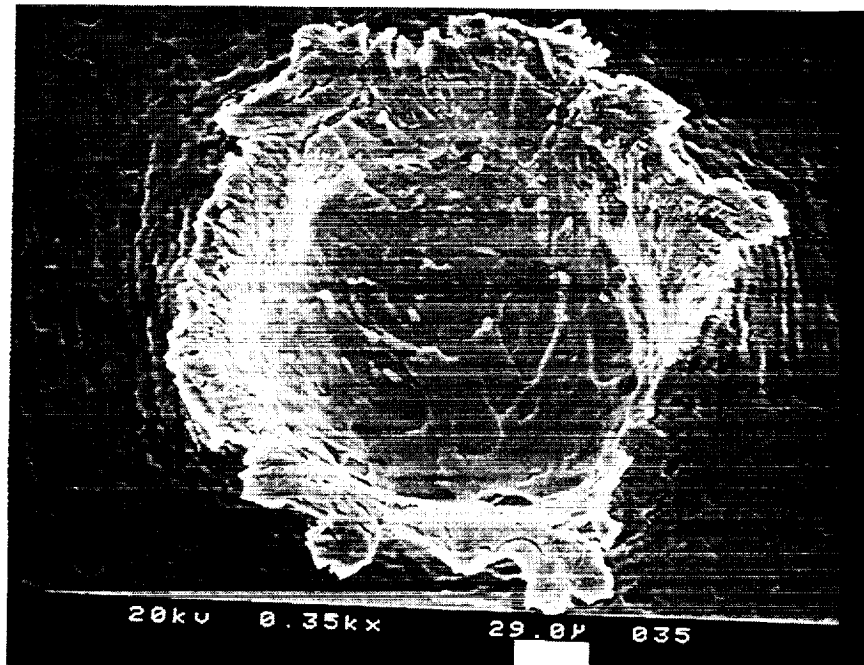
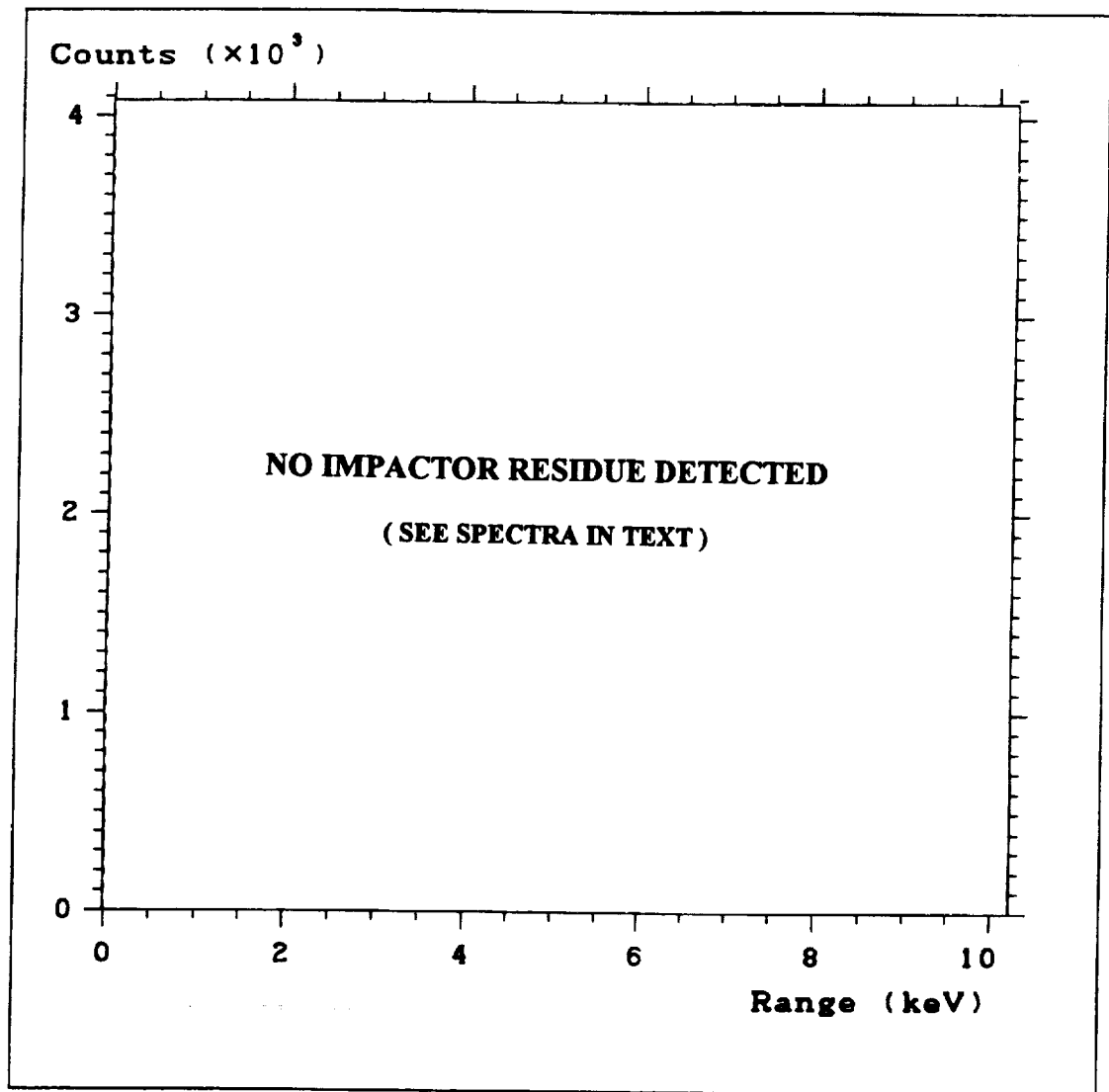


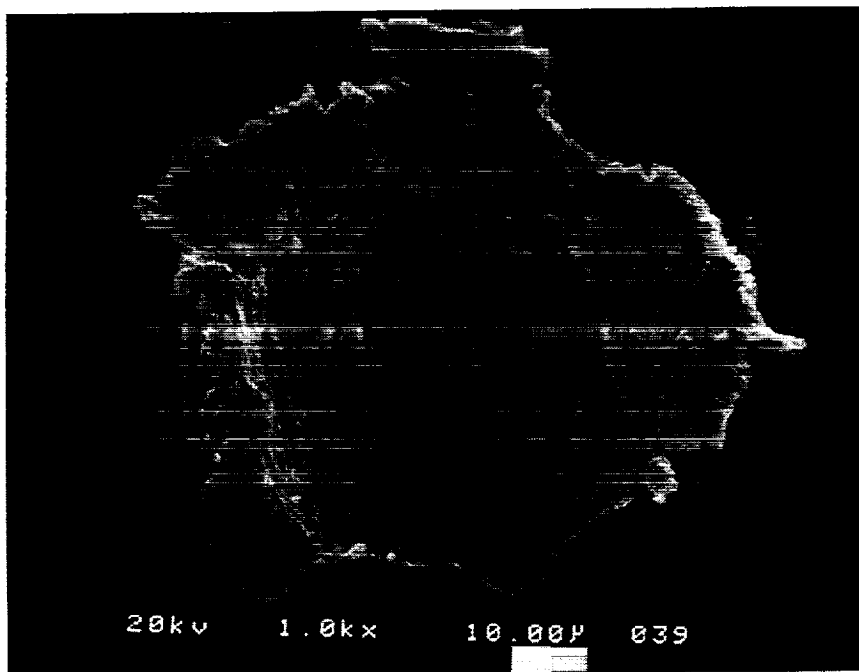
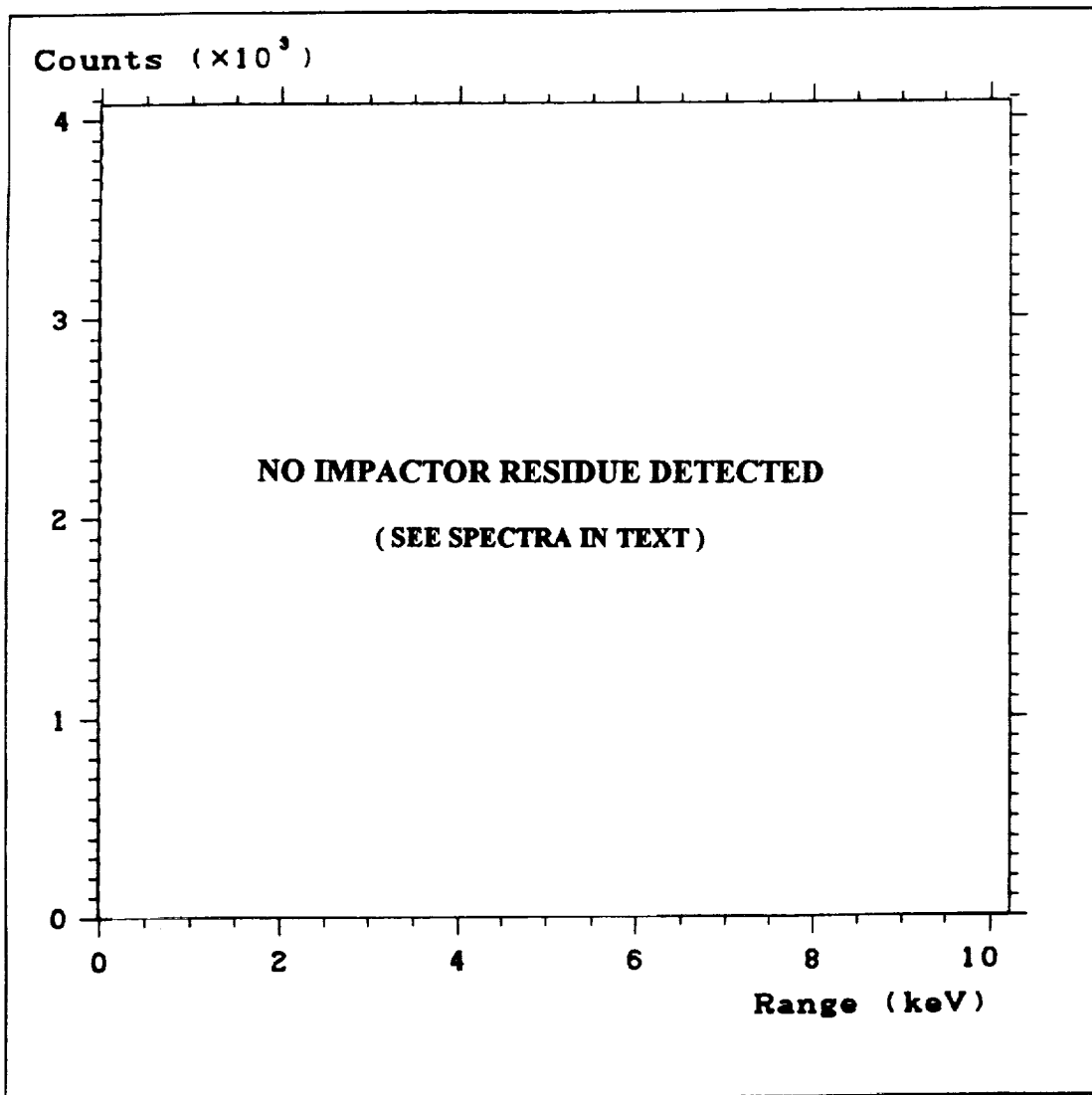






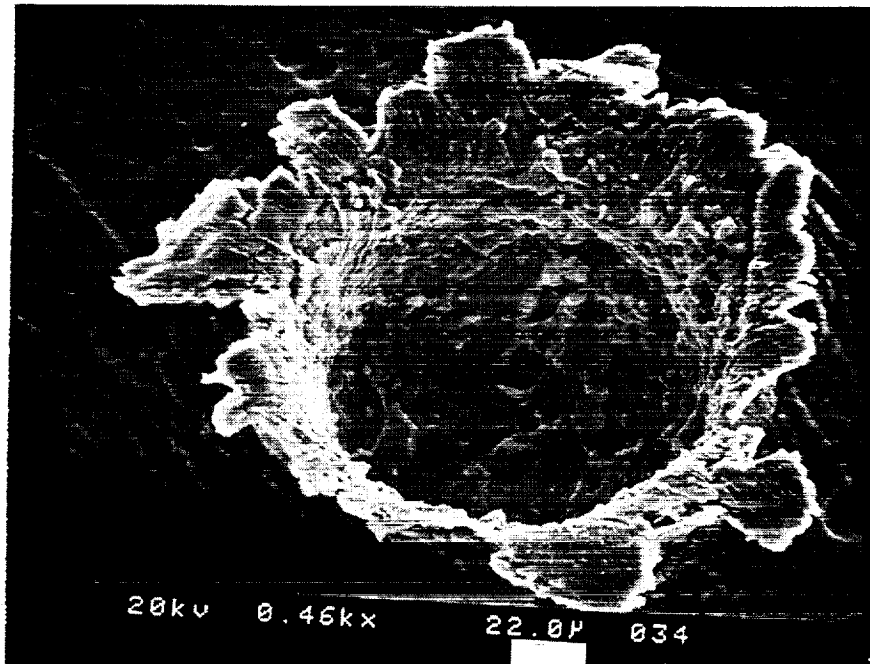
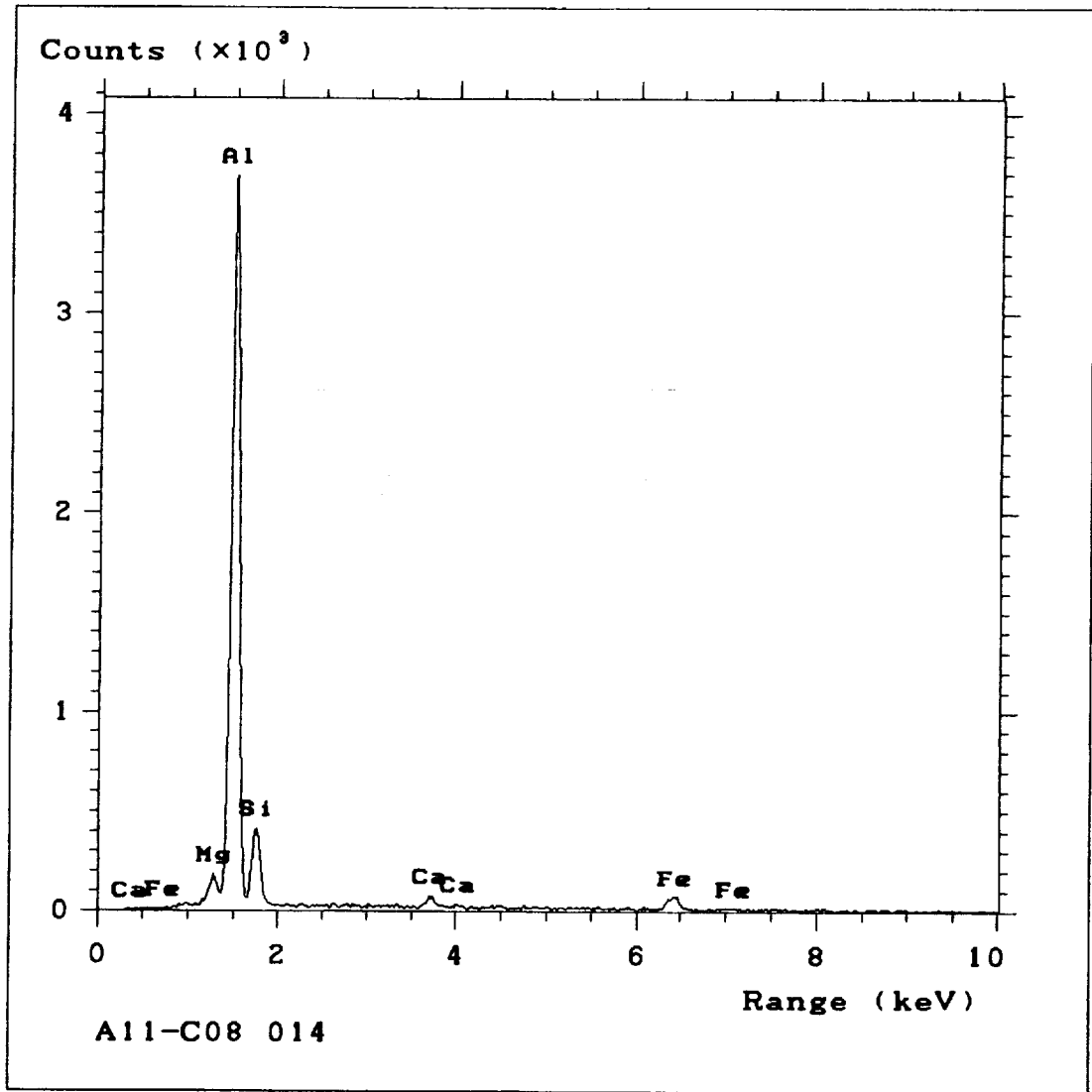






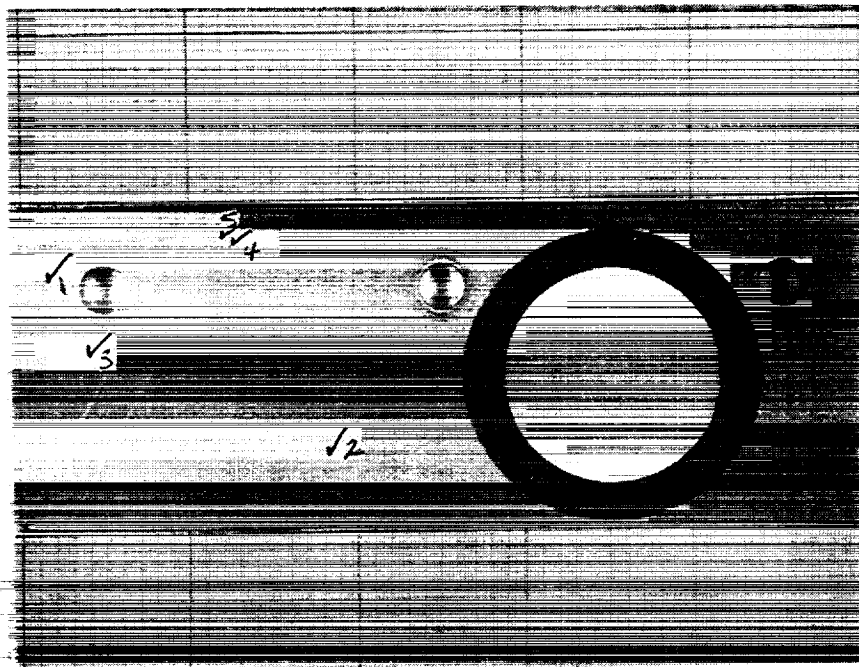
A-178

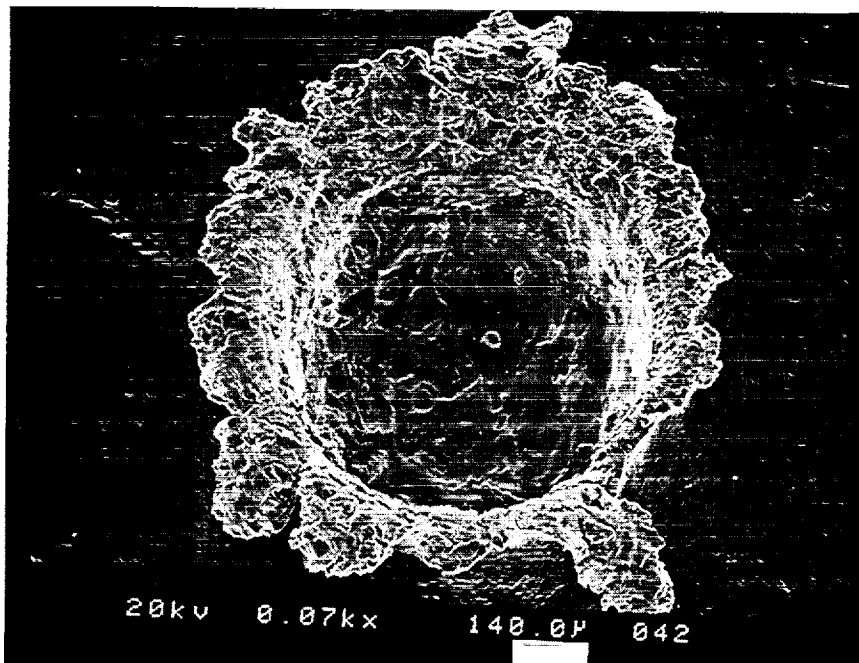
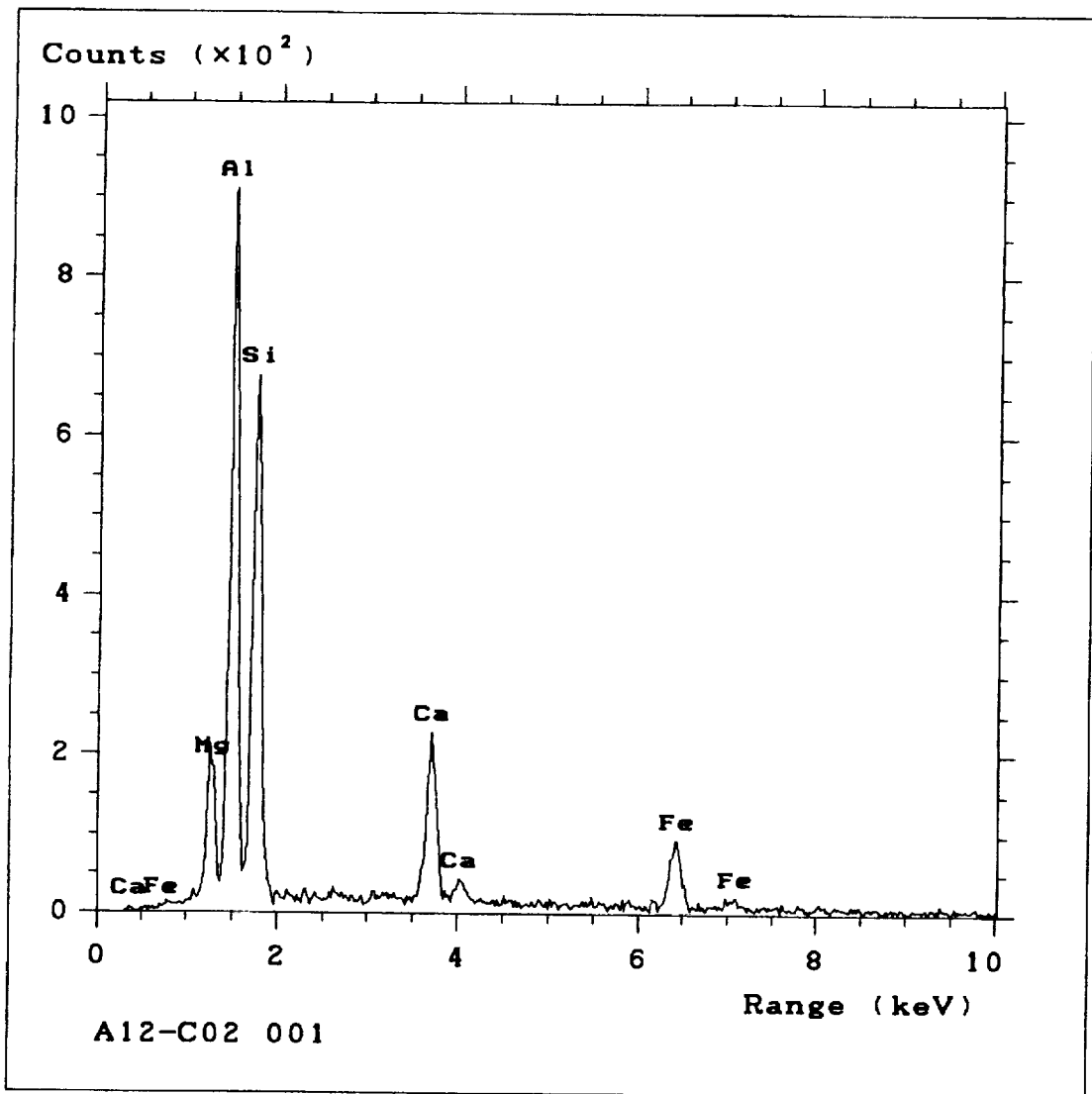
C-3

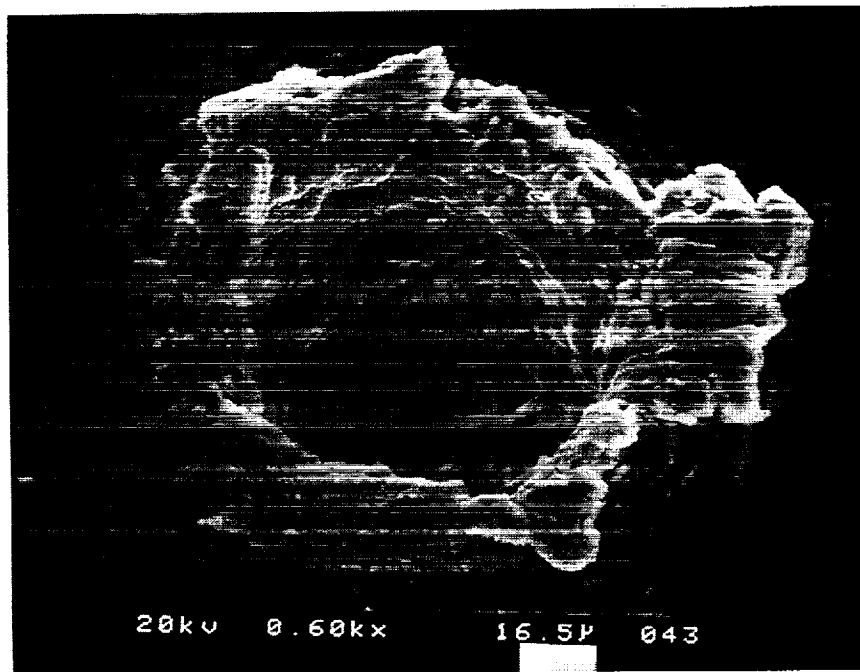
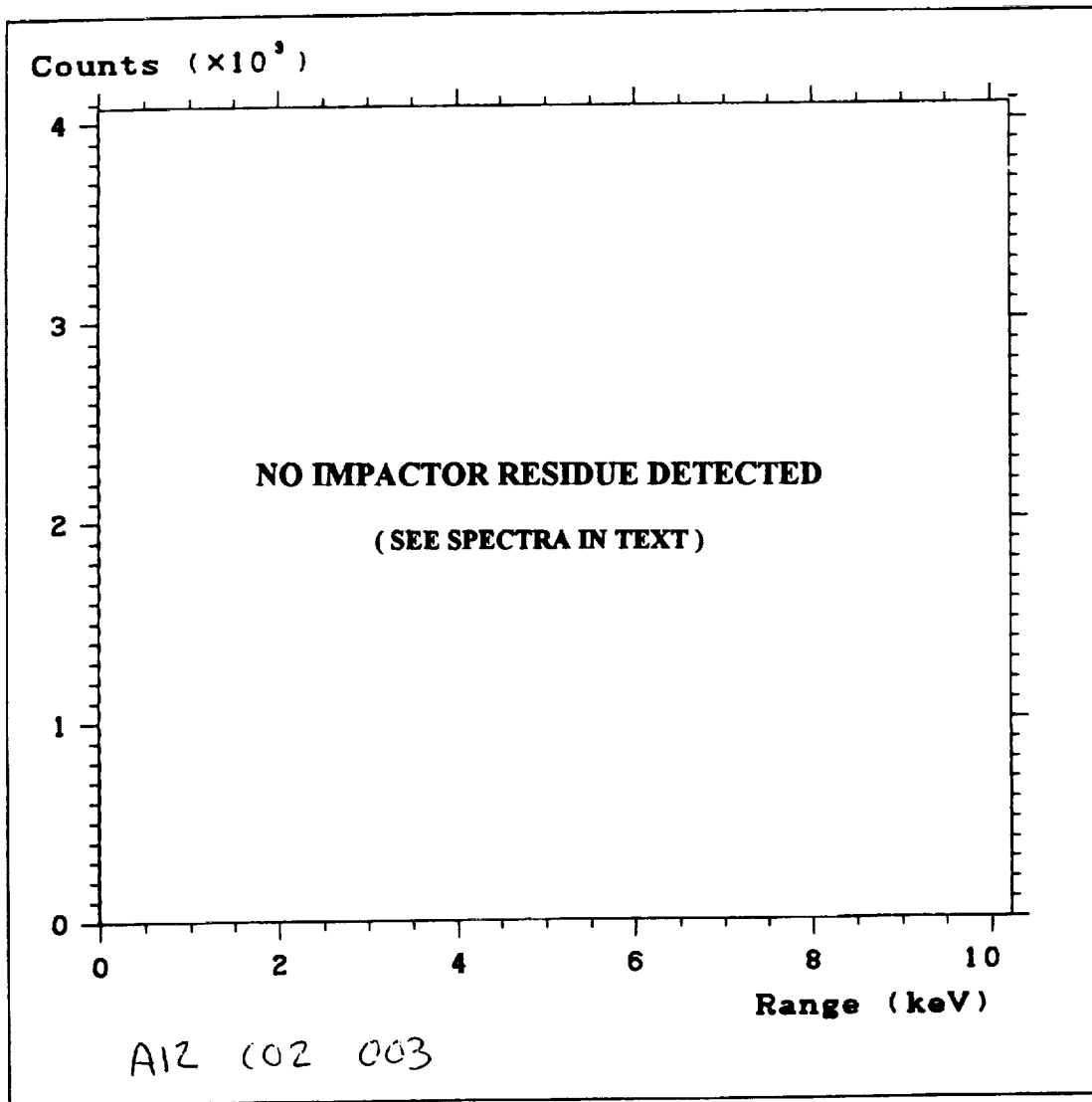


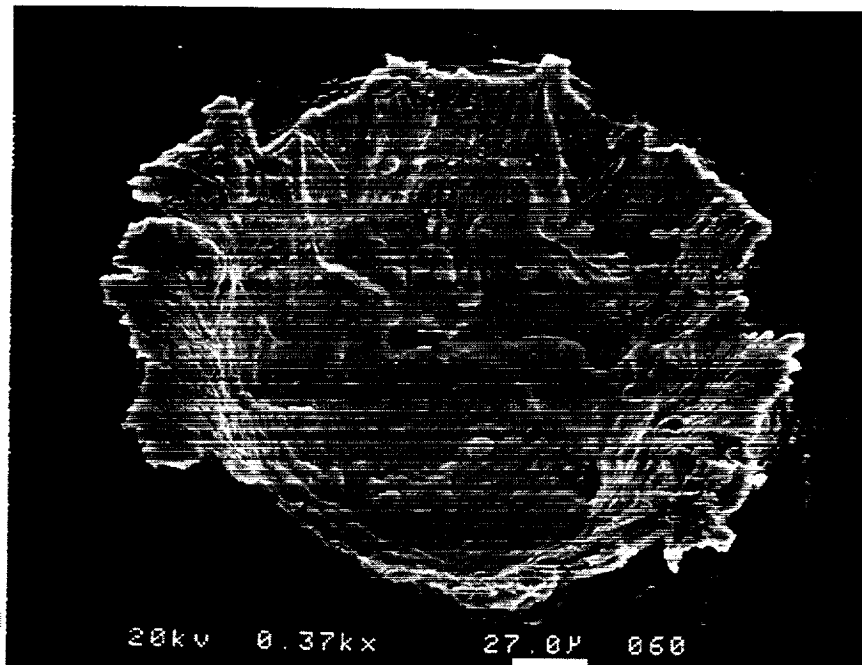
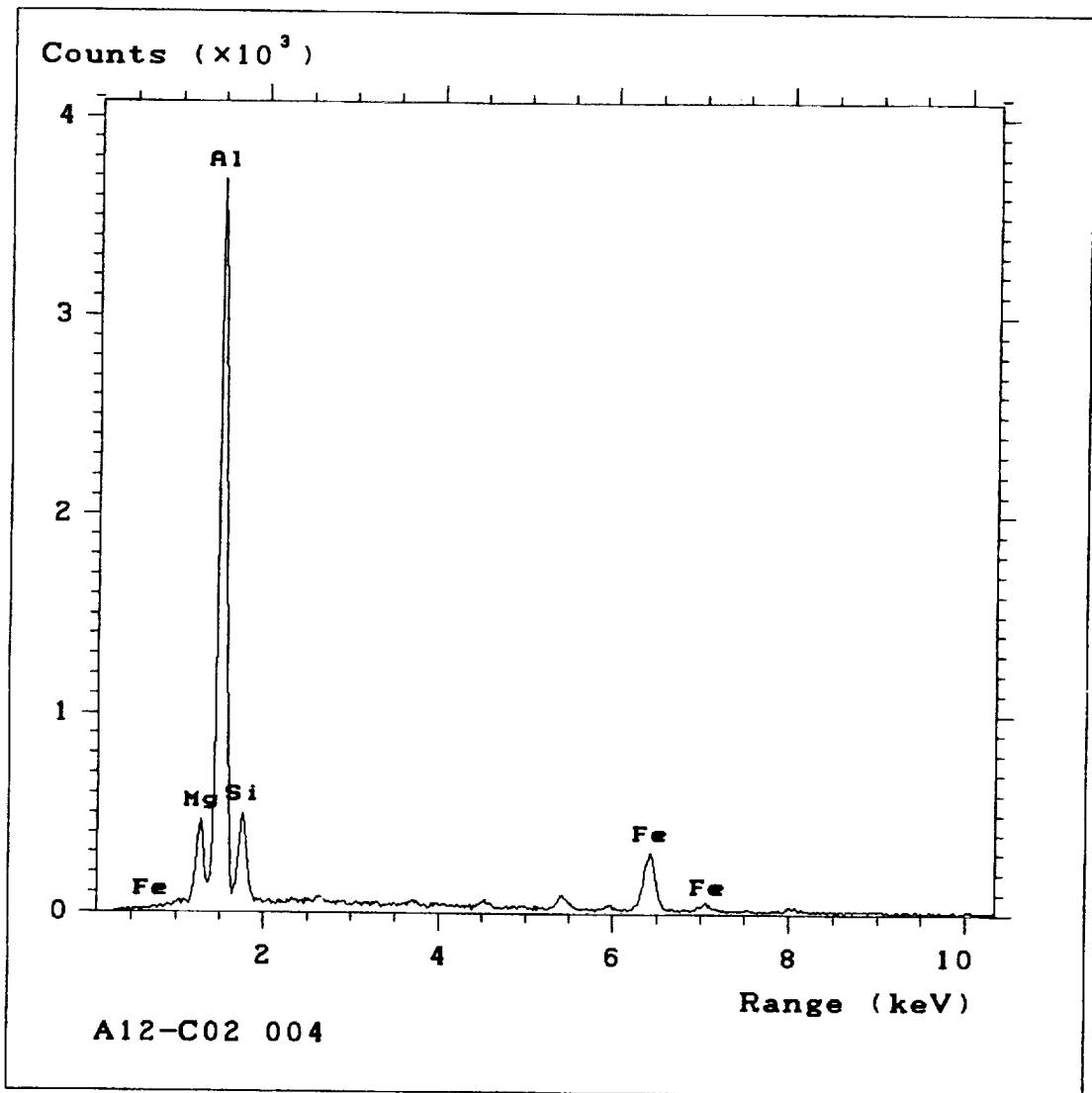
CLAMP NUMBER A12 CO2

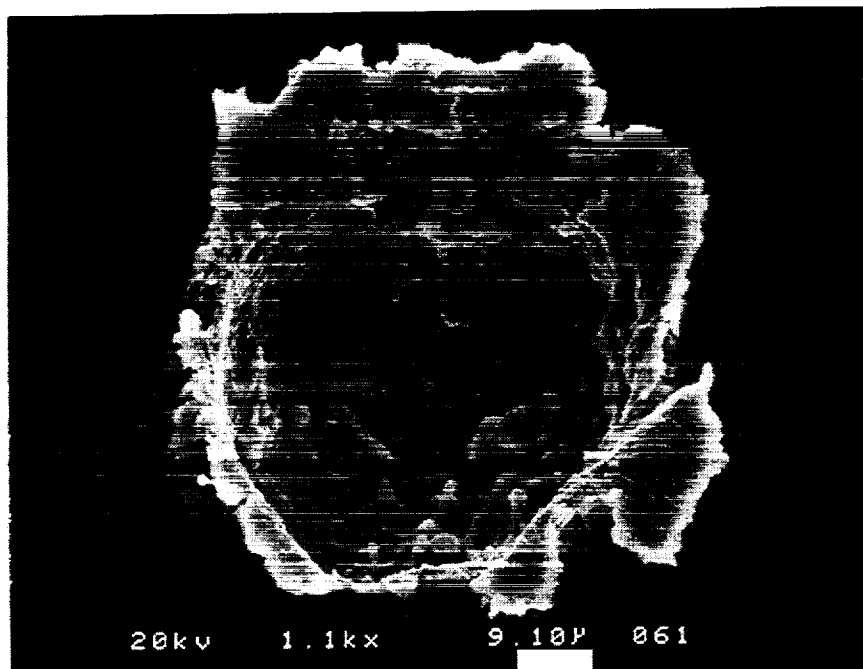
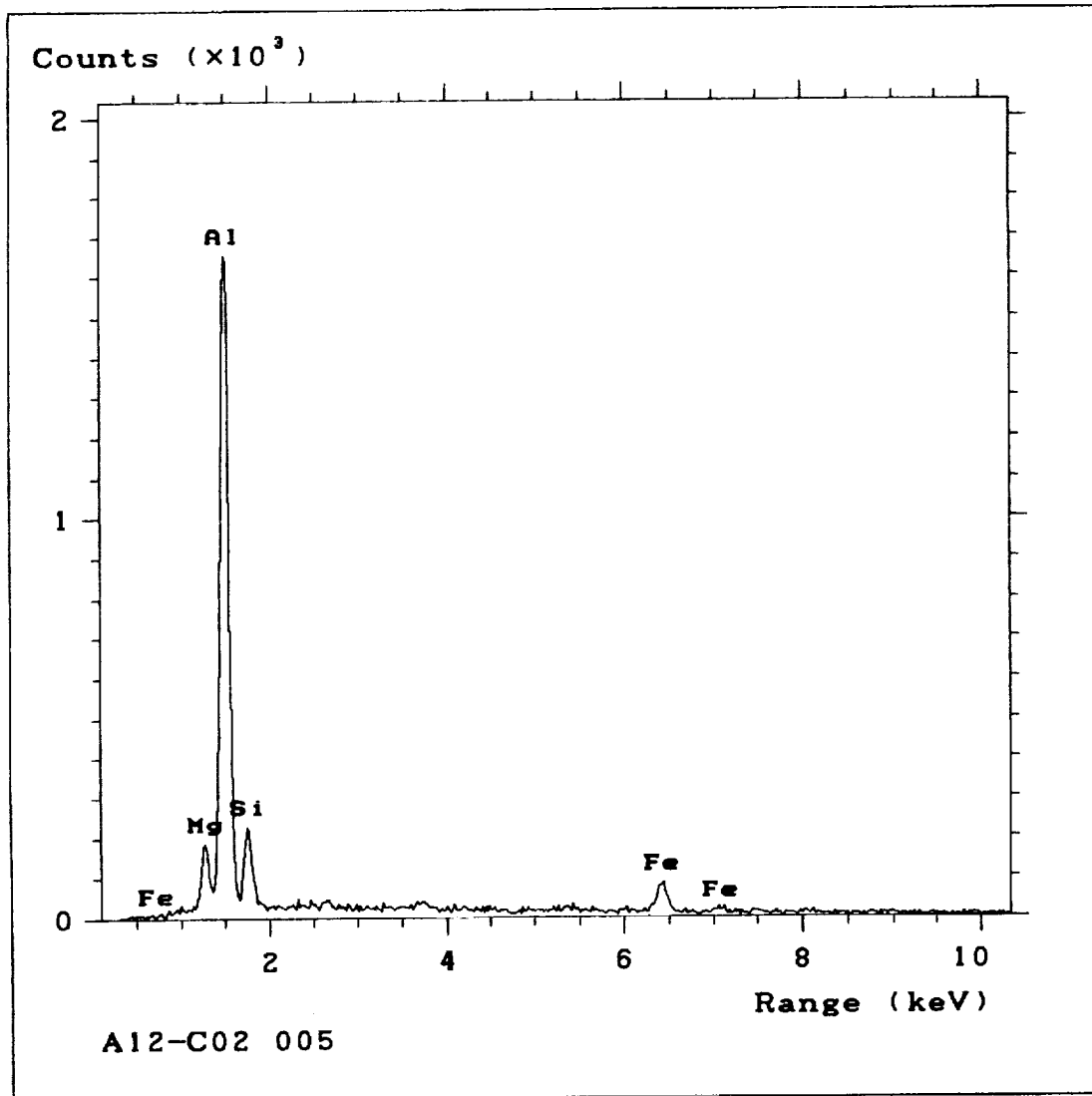
<u>IMPACT NUMBER</u>	<u>DIAMETER</u>	<u>GENERAL COMPONENTS</u>
001	900	Si, Mg, Ca, Fe
002	N/A	Clamp Flaw
003	130	Unknown
004	200	Trace
005	80	Trace











1

2

3

4

REPORT DOCUMENTATION PAGE

Form Approved
OMB No. 0704-0188

Public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302, and to the Office of Management and Budget, Paperwork Reduction Project (0704-0188), Washington, DC 20503.

1. AGENCY USE ONLY (Leave blank)	2. REPORT DATE March 1993	3. REPORT TYPE AND DATES COVERED Technical Memorandum	
4. TITLE AND SUBTITLE Analysis of Impactor Residues in Tray Clamps from the Long Duration Exposure Facility		5. FUNDING NUMBERS	
6. AUTHOR(S) Michael E. Zolensky; Ronald P. Bernhard		8. PERFORMING ORGANIZATION REPORT NUMBER S-708	
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) Solar System Exploration Division NASA/Johnson Space Center Houston, TX 77058		10. SPONSORING / MONITORING AGENCY REPORT NUMBER NASA TM 104759	
9. SPONSORING / MONITORING AGENCY NAME(S) AND ADDRESS(ES)		11. SUPPLEMENTARY NOTES Michael E. Zolensky, NASA/Johnson Space Center Ronald P. Bernhard, Lockheed Engineering & Science Co.	
12a. DISTRIBUTION / AVAILABILITY STATEMENT		12b. DISTRIBUTION CODE	
13. ABSTRACT (Maximum 200 words) The Long Duration Exposure Facility (LDEF) was placed in low Earth orbit (LEO) in 1984 and was recovered 5.7 years later. The LDEF was host to several individual experiments that were specifically designed to characterize critical aspects of meteoroid and debris environment in LEO. It was realized from the beginning, however, that the most efficient use of the satellite would be to examine the entire surface of the Earth for impact features. In this regard, particular interest has centered on common exposed materials that faced in all LDEF pointing directions. Among the most important of these materials is the tray clamps. Therefore, in an effort to understand the nature of particulates in LEO and their effects on spacecraft hardware better, we are analyzing residues found in impact features on LDEF tray clamp surfaces. This catalog presents all data from clamps from Bay A of the LDEF. Subsequent catalogs will include clamps from succeeding bays of the satellite.			
14. SUBJECT TERMS Long Duration Exposure Facility (LDEF); Earth orbit, low (LEO); meteoroids, impact damage; debris; clamps, holders (tray)			15. NUMBER OF PAGES
17. SECURITY CLASSIFICATION OF REPORT Unclassified			16. PRICE CODE
18. SECURITY CLASSIFICATION OF THIS PAGE Unclassified	19. SECURITY CLASSIFICATION OF ABSTRACT Unclassified	20. LIMITATION OF ABSTRACT UL	

Subject Category: 43